



THE DATASHEET OF SN74ALVCHR16269GR

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ALVC ***Advanced Low-Voltage CMOS*** ***Data Book***

Including SSTL, HSTL, and ALB



Printed on Recycled Paper

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INTRODUCTION

Since its inception in 1994, the Texas Instruments (TI™) ALVC (Advanced Low-Voltage CMOS) logic family has been the de facto standard for high-performance low-voltage logic. Designed for operation in the 2.3-V to 3.6-V V_{CC} range, the close to 80 functions of the ALVC family allow the design flexibility and ease needed for today's most demanding high-performance systems. For bus-interface functions, ALVC offers a current drive of 24 mA and static power consumption of 40 μ A. Bus-hold cells on the inputs of ALVC devices eliminate the need for external pullup resistors and prevent inputs from floating.

The ALVC family, which includes innovative functions for memory interleaving, multiplexing, and interlacing to SDRAMs, has gained prominence in the high-speed memory market. The ALVC family offers the industry's most complete line of high-speed memory interface logic devices. A number of ALVC devices feature series damping resistors for improved noise performance. Also, a number of devices without bus hold are ideally suited for PC100 applications.

SSTL (Stub Series-Terminated Logic) is the computer industry's leading choice for next-generation technology in high-speed memory subsystems, adopted by a JEDEC standard and endorsed by major memory module, workstation, and personal computer (PC) manufacturers. Five devices are included in the SSTL section of this data book.

ALB (Advanced Low-Voltage BiCMOS) logic is the fastest BiCMOS logic family available from TI. With clamping diodes to eliminate undershoot and overshoot, these two 3.3-V Widebus™ devices address the high-speed demands of the industry.

HSTL (High-Speed Transceiver Logic) devices accept HSTL-level inputs and produce LVTTTL-level output signals. HSTL devices have found a home in select memory-addressing applications.

For more information on these or other TI products, please consult the TI Worldwide Technical Support listing in the back of this data book, or visit the TI logic web page at <http://www.ti.com/sc/logic>.

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INTRODUCTION

These symbols, terms, and definitions are in accordance with those currently agreed upon by the JEDEC Council of the Electronic Industries Association (EIA) for use in the USA and by the International Electrotechnical Commission (IEC) for international use.

operating conditions and characteristics (in sequence by letter symbols)

C_i	Input capacitance The internal capacitance at an input of the device
C_{io}	Input/output capacitance Input-to-output internal capacitance; transcapacitance
C_o	Output capacitance The internal capacitance at an output of the device
C_{pd}	Power dissipation capacitance Used to determine the no-load dynamic power dissipation per logic function (see individual circuit pages): $P_D = C_{pd} V_{CC}^2 f + I_{CC} V_{CC}$
f_{max}	Maximum clock frequency The highest rate at which the clock input of a bistable circuit can be driven through its required sequence while maintaining stable transitions of logic level at the output with input conditions established that should cause changes of output logic level in accordance with the specification
I_{CC}	Supply current The current into* the V _{CC} supply terminal of an integrated circuit
ΔI_{CC}	Supply current change The increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V _{CC}
I_{CEX}	Output high leakage current The maximum leakage current into the collector of the pulldown output transistor when the output is high and the output forcing condition V _O = 5.5 V
I_{I(hold)}	Input hold current Input current that holds the input at the previous state when the driving device goes to a high-impedance state
I_{IH}	High-level input current The current into* an input when a high-level voltage is applied to that input
I_{IL}	Low-level input current The current into* an input when a low-level voltage is applied to that input
I_{off}	Input/output power-off leakage current The maximum leakage current into/out of the input/output transistors when forcing the input/output to 4.5 V and V _{CC} = 0 V
I_{OH}	High-level output current The current into* an output with input conditions applied that, according to the product specification, establishes a high level at the output

*Current out of a terminal is given as a negative value.

GLOSSARY

SYMBOLS, TERMS, AND DEFINITIONS

I_{OL}	Low-level output current The current into* an output with input conditions applied that, according to the product specification, establishes a low level at the output
$I_{OZ}, I_{OZPU/PD}$	Off-state (high-impedance-state) output current (of a 3-state output) The current flowing into* an output having 3-state capability with input conditions established that, according to the product specification, establishes the high-impedance state at the output
t_a	Access time The time interval between the application of a specified input pulse and the availability of valid signals at an output
t_c	Clock cycle time Clock cycle time is $1/f_{max}$.
t_{dis}	Disable time (of a 3-state or open-collector output) The propagation time between the specified reference points on the input and output voltage waveforms with the output changing from either of the defined active levels (high or low) to a high-impedance (off) state NOTE: For 3-state outputs, $t_{dis} = t_{PHZ}$ or t_{PLZ} . Open-collector outputs change only if they are low at the time of disabling, so $t_{dis} = t_{PLH}$.
t_{en}	Enable time (of a 3-state or open-collector output) The propagation time between the specified reference points on the input and output voltage waveforms with the output changing from a high-impedance (off) state to either of the defined active levels (high or low) NOTE: In the case of memories, this is the access time from an enable input (e.g., $\overline{OE}$). For 3-state outputs, $t_{en} = t_{PZH}$ or t_{PZL} . Open-collector outputs change only if they are responding to data that would cause the output to go low, so $t_{en} = t_{PHL}$.
t_h	Hold time The time interval during which a signal is retained at a specified input terminal after an active transition occurs at another specified input terminal NOTES: 1. The hold time is the actual time interval between two signal events and is determined by the system in which the digital circuit operates. A minimum value is specified that is the shortest interval for which correct operation of the digital circuit is to be expected. 2. The hold time may have a negative value in which case the minimum limit defines the longest interval (between the release of the signal and the active transition) for which correct operation of the digital circuit is to be expected.
t_{pd}	Propagation delay time The time between the specified reference points on the input and output voltage waveforms with the output changing from one defined level (high or low) to the other defined level ($t_{pd} = t_{PHL}$ or t_{PLH})
t_{PHL}	Propagation delay time, high-to-low level output The time between the specified reference points on the input and output voltage waveforms with the output changing from the defined high level to the defined low level
t_{PHZ}	Disable time (of a 3-state output) from high level The time interval between the specified reference points on the input and the output voltage waveforms with the 3-state output changing from the defined high level to the high-impedance (off) state

*Current out of a terminal is given as a negative value.



t_{PLH}	Propagation delay time, low-to-high level output The time between the specified reference points on the input and output voltage waveforms with the output changing from the defined low level to the defined high level
t_{PLZ}	Disable time (of a 3-state output) from low level The time interval between the specified reference points on the input and the output voltage waveforms with the 3-state output changing from the defined low level to the high-impedance (off) state
t_{PZH}	Enable time (of a 3-state output) to high level The time interval between the specified reference points on the input and output voltage waveforms with the 3-state output changing from the high-impedance (off) state to the defined high level
t_{PZL}	Enable time (of a 3-state output) to low level The time interval between the specified reference points on the input and output voltage waveforms with the 3-state output changing from the high-impedance (off) state to the defined low level
t_{sk(o)}	Output skew The difference between any two propagation delay times when a single switching input or multiple inputs switching simultaneously cause multiple outputs to switch, as observed across all switching output. This parameter is used to describe the fanout capability of a clock driver and is of concern when making decisions on clock buffering and distribution networks.
t_{su}	Setup time The time interval between the application of a signal at a specified input terminal and a subsequent active transition at another specified input terminal NOTES: 1. The setup time is the actual time interval between two signal events and is determined by the system in which the digital circuit operates. A minimum value is specified that is the shortest interval for which correct operation of the digital circuit is to be expected. 2. The setup time may have a negative value, in which case the minimum limit defines the longest interval (between the active transition and the application of the other signal) for which correct operation of the digital circuit is to be expected.
t_w	Pulse duration (width) The time interval between specified reference points on the leading and trailing edges of the pulse waveform
V_{IH}	High-level input voltage An input voltage within the more positive (less negative) of the two ranges of values used to represent the binary variables NOTE: A minimum is specified that is the least-positive value of high-level input voltage for which operation of the logic element within specification limits is to be expected.
V_{IL}	Low-level input voltage An input voltage within the less positive (more negative) of the two ranges of values used to represent the binary variables NOTE: A maximum is specified that is the most-positive value of low-level input voltage for which operation of the logic element within specification limits is to be expected.
V_{OH}	High-level output voltage The voltage at an output terminal with input conditions applied that, according to product specification, establishes a high level at the output

GLOSSARY

SYMBOLS, TERMS, AND DEFINITIONS

V_{OL} Low-level output voltage

The voltage at an output terminal with input conditions applied that, according to product specification, establishes a low level at the output

V_{IT+} Positive-going input threshold level

The voltage level at a transition-operated input that causes operation of the logic element according to specification as the input voltage rises from a level below the negative-going threshold voltage, V_{IT-}

V_{IT-} Negative-going input threshold level

The voltage level at a transition-operated input that causes operation of the logic element according to specification as the input voltage falls from a level above the positive-going threshold voltage, V_{IT+}

The following symbols are used in function tables on TI data sheets:

H	=	high level (steady state)
L	=	low level (steady state)
↑	=	transition from low to high level
↓	=	transition from high to low level
→	=	value/level or resulting value/level is routed to indicated destination
↶	=	value/level is re-entered
X	=	irrelevant (any input, including transitions)
Z	=	off (high-impedance) state of a 3-state output
a . . . h	=	the level of steady-state inputs A through H, respectively
Q_0	=	level of Q before the indicated steady-state input conditions were established
$\overline{Q}_0$	=	complement of Q_0 or level of $\overline{Q}$ before the indicated steady-state input conditions were established
Q_n	=	level of Q before the most recent active transition indicated by ↓ or ↑
	=	one high-level pulse
	=	one low-level pulse
Toggle	=	each output changes to the complement of its previous level on each active transition indicated by ↓ or ↑

If, in the input columns, a row contains only the symbols H, L, and/or X, this means the indicated output is valid whenever the input configuration is achieved and regardless of the sequence in which it is achieved. The output persists so long as the input configuration is maintained.

If, in the input columns, a row contains H, L, and/or X together with ↑ and/or ↓, this means the output is valid whenever the input configuration is achieved but the transition(s) must occur following the achievement of the steady-state levels. If the output is shown as a level (H, L, Q_0 , or $\overline{Q}_0$), it persists so long as the steady-state input levels and the levels that terminate indicated transitions are maintained. Unless otherwise indicated, input transitions in the opposite direction to those shown have no effect at the output. (If the output is shown as a pulse,  or , the pulse follows the indicated input transition and persists for an interval dependent on the circuit.)

EXPLANATION OF FUNCTION TABLES

Among the most complex function tables are those of the shift registers. These embody most of the symbols used in any of the function tables, plus more. Below is the function table of a 4-bit bidirectional universal shift register.

FUNCTION TABLE													
INPUTS									OUTPUTS				
CLEAR	MODE		CLOCK	SERIAL		PARALLEL				QA	QB	QC	QD
	S1	S0		LEFT	RIGHT	A	B	C	D				
L	X	X	X	X	X	X	X	X	X	L	L	L	L
H	X	X	L	X	X	X	X	X	X	QA0	QB0	QC0	QD0
H	H	H	↑	X	X	a	b	c	d	a	b	c	d
H	L	H	↑	X	H	H	H	H	H	H	QAn	QBn	QCn
H	L	H	↑	X	L	L	L	L	L	L	QAn	QBn	QCn
H	H	L	↑	H	X	X	X	X	X	QBn	QCn	QDn	H
H	H	L	↑	L	X	X	X	X	X	QBn	QCn	QDn	L
H	L	L	X	X	X	X	X	X	X	QA0	QB0	QC0	QD0

The first line of the table represents a synchronous clearing of the register and says that if clear is low, all four outputs will be reset low regardless of the other inputs. In the following lines, clear is inactive (high) and so has no effect.

The second line shows that so long as the clock input remains low (while clear is high), no other input has any effect and the outputs maintain the levels they assumed before the steady-state combination of clear high and clock low was established. Since on other lines of the table only the rising transition of the clock is shown to be active, the second line implicitly shows that no further change in the outputs occurs while the clock remains high or on the high-to-low transition of the clock.

The third line of the table represents synchronous parallel loading of the register and says that if S1 and S0 are both high then, without regard to the serial input, the data entered at A is at output Q_A, data entered at B is at Q_B, and so forth, following a low-to-high clock transition.

The fourth and fifth lines represent the loading of high- and low-level data, respectively, from the shift-right serial input and the shifting of previously entered data one bit; data previously at Q_A is now at Q_B, the previous levels of Q_B and Q_C are now at Q_C and Q_D, respectively, and the data previously at Q_D is no longer in the register. This entry of serial data and shift takes place on the low-to-high transition of the clock when S1 is low and S0 is high and the levels at inputs A through D have no effect.

The sixth and seventh lines represent the loading of high- and low-level data, respectively, from the shift-left serial input and the shifting of previously entered data one bit; data previously at Q_B is now at Q_A, the previous levels of Q_C and Q_D are now at Q_B and Q_C, respectively, and the data previously at Q_A is no longer in the register. This entry of serial data and shift takes place on the low-to-high transition of the clock when S1 is high and S0 is low and the levels at inputs A through D have no effect.

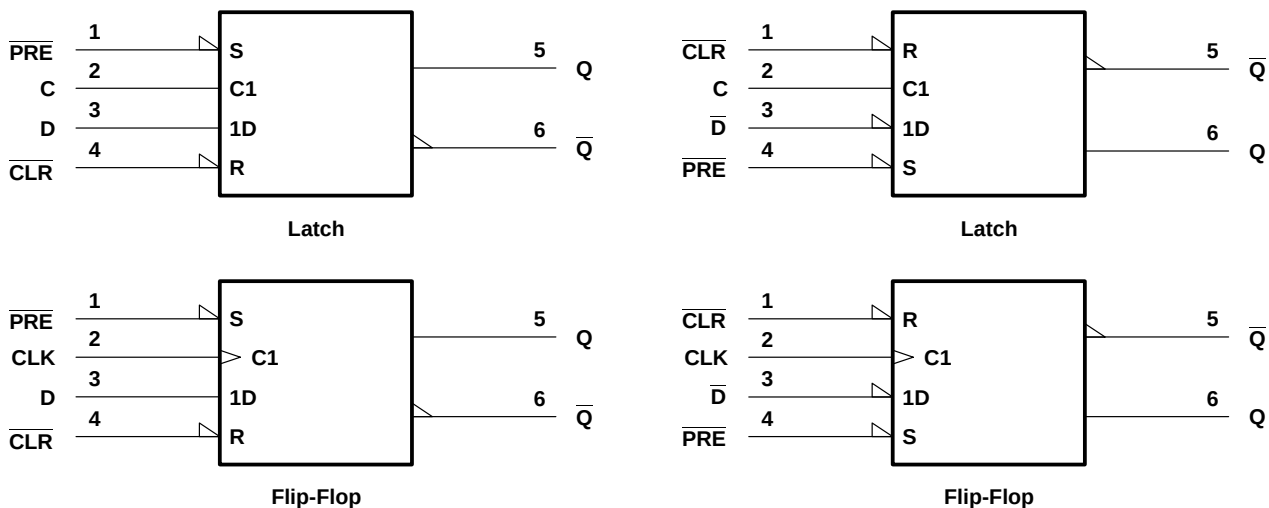
The last line shows that as long as both inputs are low, no other input has any effect and, as in the second line, the outputs maintain the levels they assumed before the steady-state combination of clear high and both mode inputs low was established.

The function table functional tests do not reflect all possible combinations or sequential modes.

It is normal TI practice to name the outputs and other inputs of a D-type flip-flop or latch and to draw its logic symbol based on the assumption of true data (D) inputs. Outputs that produce data in phase with the data inputs are called Q and those producing complementary data are called $\bar{Q}$. An input that causes a Q output to go high or a $\bar{Q}$ output to go low is called preset (PRE). An input that causes a $\bar{Q}$ output to go high or a Q output to go low is called clear (CLR). Bars are used over these pin names ($\overline{\text{PRE}}$ and $\overline{\text{CLR}}$) if they are active low.

The devices on several data sheets are second-source designs, and the pin-name conventions used by the original manufacturers have been retained. That makes it necessary to designate the inputs and outputs of the inverting circuits $\bar{D}$ and $\bar{Q}$.

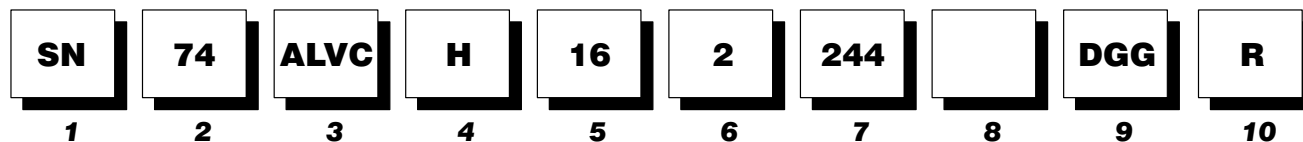
In some applications, it may be advantageous to redesignate the data input from D to $\bar{D}$ or vice versa. In that case, all the other inputs and outputs should be renamed as shown below. Also shown are corresponding changes in the graphical symbols. Arbitrary pin numbers are shown.



The figures show that when Q and $\bar{Q}$ exchange names, the preset and clear pins also exchange names. The polarity indicators ($\triangle$) on $\overline{\text{PRE}}$ and $\overline{\text{CLR}}$ remain, as these inputs are still active low, but the presence or absence of the polarity indicator changes at D (or $\bar{D}$), Q, and $\bar{Q}$. Pin 5 (Q or $\bar{Q}$) is still in phase with the data input (D or $\bar{D}$); their active levels change together.

DEVICE NAMES AND PACKAGE DESIGNATORS

Example:



1 Standard Prefix

Example: SNJ – Conforms to MIL-PRF-38535 (QML)

2 Temperature Range

Examples: 54 – Military
74 – Commercial

3 Family

Examples: Blank – Transistor-Transistor Logic
ABT – Advanced BiCMOS Technology
ABTE – Advanced BiCMOS Technology/
Enhanced Transceiver Logic
AC/ACT – Advanced CMOS Logic
AHC/AHCT – Advanced High-Speed CMOS Logic
ALB – Advanced Low-Voltage BiCMOS
ALS – Advanced Low-Power Schottky Logic
ALVC – Advanced Low-Voltage CMOS Technology
AS – Advanced Schottky Logic
AVC – Advanced Very Low-Voltage CMOS Logic
BCT – BiCMOS Bus-Interface Technology
CBT – Crossbar Technology
CBTLV – Low-Voltage Crossbar Technology
F – F Logic
FB – Backplane Transceiver Logic/Futurebus+
GTL – Gunning Transceiver Logic
HC/HCT – High-Speed CMOS Logic
HSTL – High-Speed Transceiver Logic
LS – Low-Power Schottky Logic
LV – Low-Voltage CMOS Technology
LVC – Low-Voltage CMOS Technology
LVT – Low-Voltage BiCMOS Technology
S – Schottky Logic
SSTL – Stub Series-Terminated Logic
TVC – Translation Voltage Clamp Logic

4 Special Features

Examples: Blank = No Special Features
D – Level-Shifting Diode (CBTD)
H – Bus Hold (ALVCH)
R – Damping Resistor on Inputs/Outputs (LVCR)
S – Schottky Clamping Diode (CBTS)

5 Bit Width

Examples: Blank = Gates, MSI, and Octals
1G – Single Gate
8 – Octal IEEE 1149.1 (JTAG)
16 – Widebus™ (16, 18, and 20 bit)
18 – Widebus IEEE 1149.1 (JTAG)
32 – Widebus+™ (32 and 36 bit)

6 Options

Examples: Blank = No Options
2 – Series-Damping Resistor on Outputs
4 – Level Shifter
25 – 25-Ω Line Driver

7 Function

Examples: 244 – Noninverting Buffer/Driver
374 – D-Type Flip-Flop
573 – D-Type Transparent Latch
640 – Inverting Transceiver

8 Device Revision

Examples: Blank = No Revision
Letter Designator A–Z

9 Packages

Examples: D, DW – Small-Outline Integrated Circuit (SOIC)
DB, DL – Shrink Small-Outline Package (SSOP)
DBB, DGV – Thin Very Small-Outline Package (TVSOP)
DBQ – Quarter-Size Outline Package (QSOP)
DBV, DCK – Small-Outline Transistor Package (SOT)
DGG, PW – Thin Shrink Small-Outline Package (TSSOP)
FK – Leadless Ceramic Chip Carrier (LCCC)*
FN – Plastic Leaded Chip Carrier (PLCC)
GB – Ceramic Pin Grid Array (CPGA)*
GKE, GKF – MicroStar BGA™ Low-Profile Fine-Pitch
Ball Grid Array (LFBGA)
HFP, HS, HT, HV – Ceramic Quad Flatpack (CQFP)*
J, JT – Ceramic Dual-In-Line Package (CDIP)*
N, NP, NT – Plastic Dual-In-Line Package (PDIP)
NS, PS – Small-Outline Package (SOP)
PAG, PAH, PCA, PCB, PM, PN, PZ – Thin Quad Flatpack
(TQFP) or Thin Shrink Small-Outline Package (TSSOP)
PH, PQ, RC – Quad Flatpack (QFP)
W, WA, WD – Ceramic Flatpack (CFP)*

* Military Only

10 Tape and Reel

Devices in the DB and PW package types include the R designation for reeled product. Existing products designated as LE may maintain that designation, but are being converted to R.

Examples:

Existing Nomenclature – SN74LVTxxxDBLE

New Nomenclature – SN74LVTxxxADBR

LE – Left Embossed (valid for DB and PW packages only)

R – Standard (valid for all surface-mount packages
except some DB and PW devices)

There is no functional difference between LE and R designated products, with respect to the carrier tape, cover tape, or reels used.

MicroStar BGA, Widebus, and Widebus+ are trademarks of Texas Instruments Incorporated.



NOTIFICATION OF PACKAGE NOMENCLATURE ALIAS (for Standard Linear and Logic device names of greater than 18 characters)

TI is converting from its current order-entry system to a more advanced system. This conversion requires modifications, both internal and external, to TI's current business processes. This new system will ultimately provide significant improvements to all facets of TI's business – from production, to order entry, to logistics. One change required is a limitation of TI part numbers to no more than 18 characters in length. Based on customer inputs, Standard Linear and Logic determined the least disruptive implementations as outlined below:

1. Package alias

TI will use a package alias to denote specific package types for devices currently exceeding 18 characters in length. Table 1 shows a mapping of package codes to an alias single-character representation.

Table 1

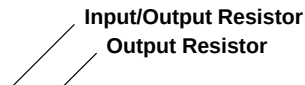
CURRENT PACKAGE CODE	ALIAS
DL	L
DGG/DBB	G
DGV	V
DLR	LR – tape/reel packing
DGGR/DBBR	GR – tape/reel packing
DGVR	VR – tape/reel packing

Current: SN74 ALVCH 162269A DGGR

New: SN74 ALVCH 162269A GR

2. Resistor-option nomenclature

For devices greater than 18 characters with input and output resistors, TI will adopt a simplified nomenclature to designate the resistor option. This will eliminate the redundant “2” (designating output resistors) when the part number also contains an “R” (designating input/output resistors).



Current: SN74 ALVCH R 16 2 245 A

New: SN74 ALVCH R 16 245 A

There is no change to the device or data-sheet electrical parameters. The packages involved and the changes in nomenclature are noted in Table 1.

These nomenclature changes are being gradually implemented. The first customer-visible conversions for TI logic devices will be made to data sheets. Over the next few months, TI logic data sheets will be updated. These changes in device nomenclature do not reflect a change in device performance or process characteristics.

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ALVC Gates/Octals	2
ALVC Widebus™/Widebus+™	3
ALVC Widebus™ With Series Damping Resistors	4
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SSTL	6
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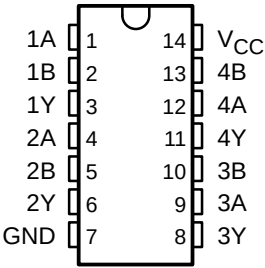
SN74ALVC00

QUADRUPLE 2-INPUT POSITIVE-NAND GATE

SCES115C – JULY 1997 – REVISED AUGUST 1998

- **EPIC™** (Enhanced-Performance Implanted CMOS) Submicron Process
- **ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)**
- **Latch-Up Performance Exceeds 250 mA Per JESD 17**
- **Package Options Include Plastic Small-Outline (D), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages**

D, DGV, OR PW PACKAGE
(TOP VIEW)



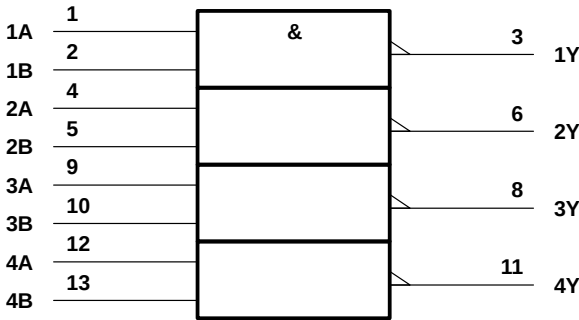
description

This quadruple 2-input positive-NAND gate is designed for 1.65-V to 3.6-V V_{CC} operation. The SN74ALVC00 performs the Boolean function $Y = \overline{A \bullet B}$ or $Y = \overline{A} + \overline{B}$ in positive logic. The SN74ALVC00 is characterized for operation from -40°C to 85°C .

FUNCTION TABLE
(each gate)

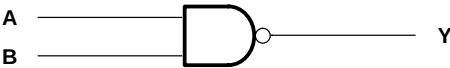
INPUTS		OUTPUT
A	B	Y
H	H	L
L	X	H
X	L	H

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram, each gate (positive logic)



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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SN74ALVC00

QUADRUPLE 2-INPUT POSITIVE-NAND GATE

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): D package	127°C/W
DGV package	182°C/W
PW package	170°C/W

Storage temperature range, T_{stg} –65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate	0	5	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

SN74ALVC00

QUADRUPLE 2-INPUT POSITIVE-NAND GATE

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	10			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	V _I = V _{CC} or GND	3.3 V	4.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V ± 0.15 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A or B	Y	1	4.4	1	2.8	3.2		1	3	ns

operating characteristics, T_A = 25°C

PARAMETER	TEST CONDITIONS	V _{CC} = 1.8 V ± 0.15 V	V _{CC} = 2.5 V ± 0.2 V	V _{CC} = 3.3 V ± 0.3 V	UNIT
		TYP	TYP	TYP	
C _{pd} Power dissipation capacitance per gate	C _L = 0, f = 10 MHz	20	21	23	pF



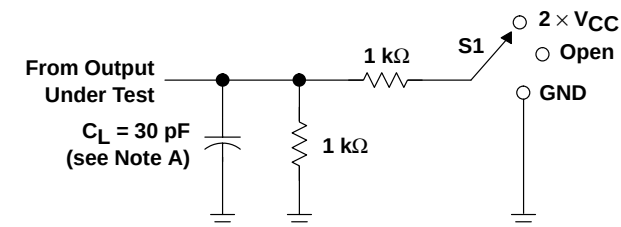
SN74ALVC00

QUADRUPLE 2-INPUT POSITIVE-NAND GATE

SCES115C – JULY 1997 – REVISED AUGUST 1998

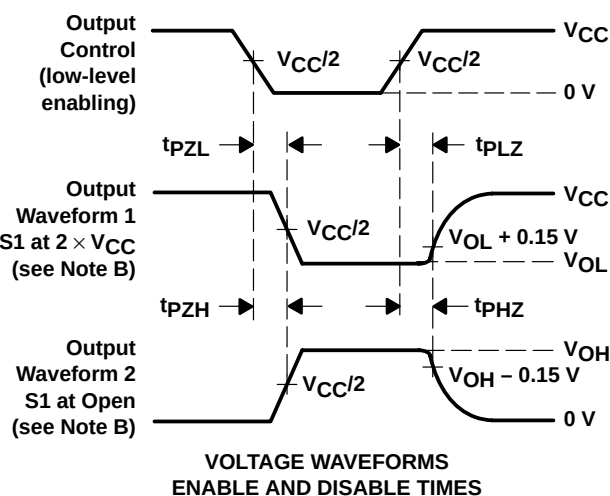
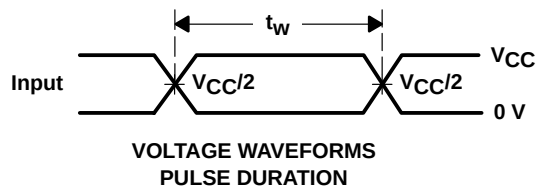
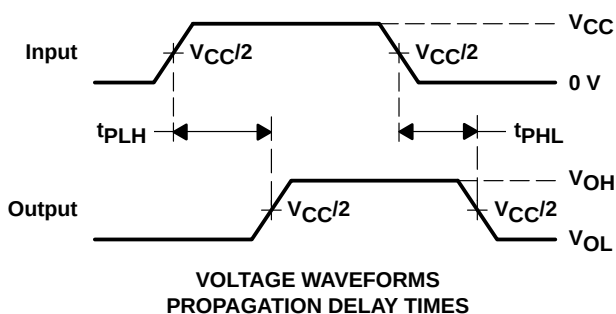
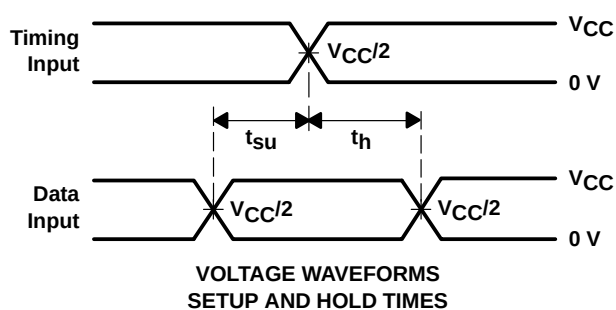
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}$$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times$ V_{CC}
t_{PHZ}/t_{PHL}	Open

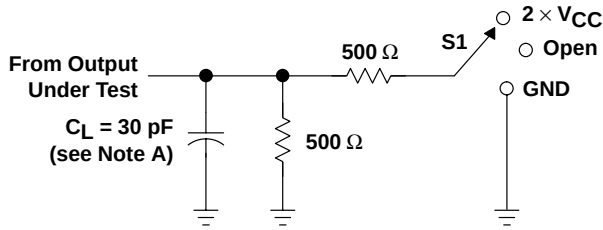


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

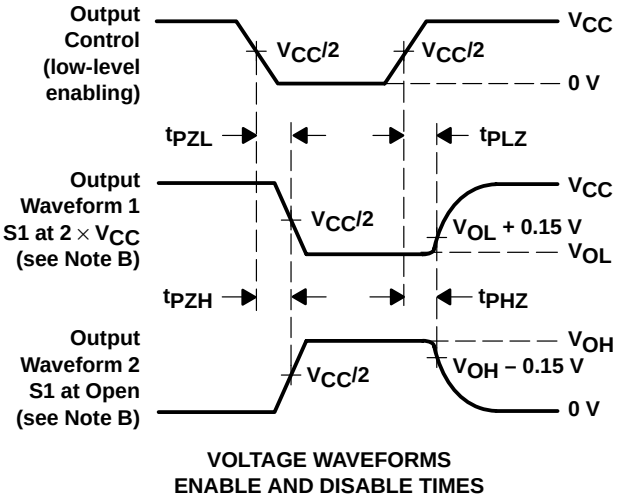
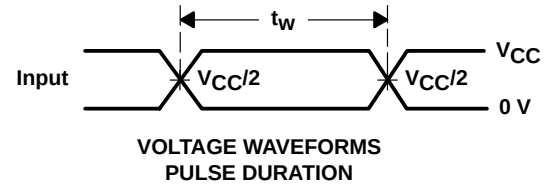
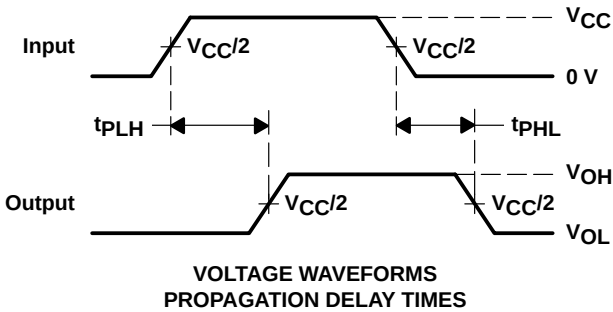
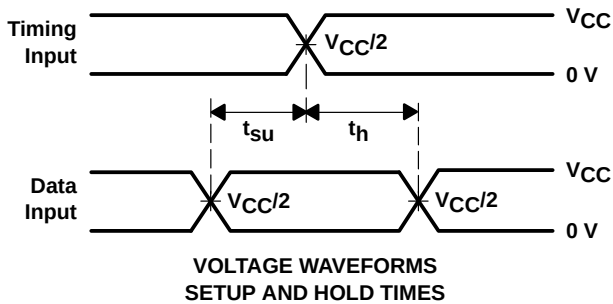
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

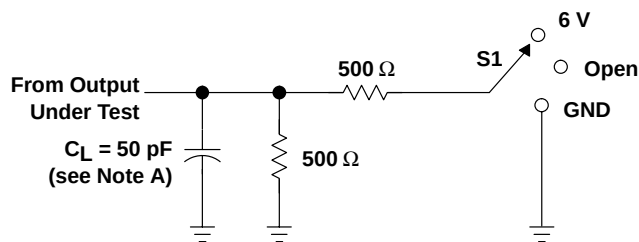
SN74ALVC00

QUADRUPLE 2-INPUT POSITIVE-NAND GATE

SCES115C – JULY 1997 – REVISED AUGUST 1998

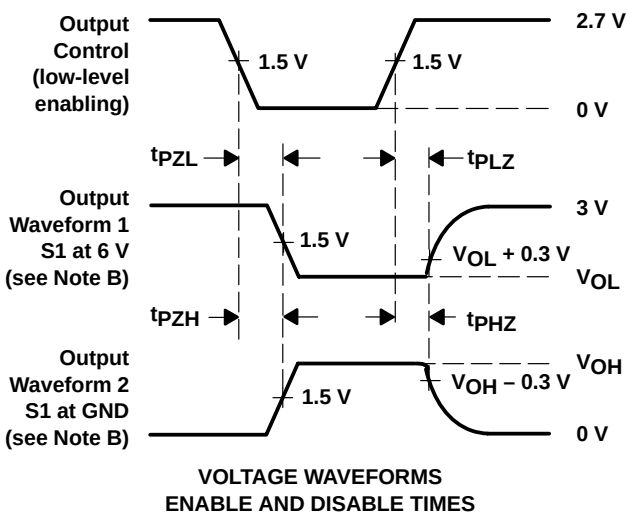
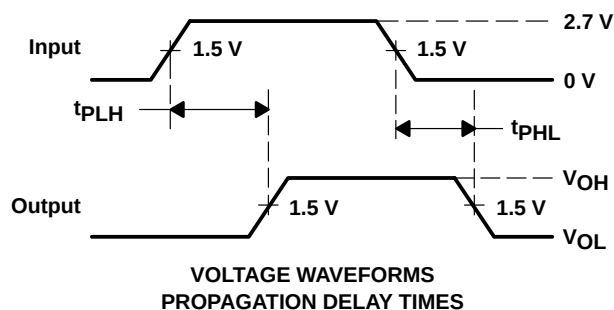
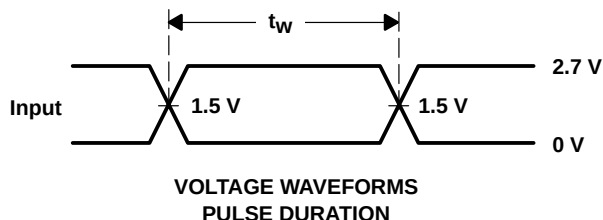
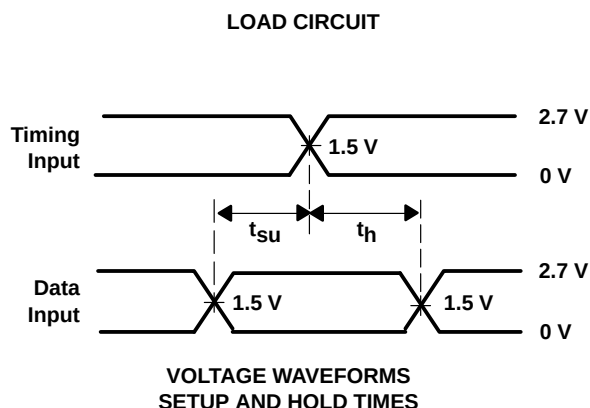
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND

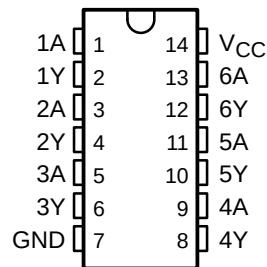


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

- **EPIC™** (Enhanced-Performance Implanted CMOS) Submicron Process
- **ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)**
- **Latch-Up Performance Exceeds 250 mA Per JESD 17**
- **Package Options Include Plastic Small-Outline (D), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages**

**D, DGV, OR PW PACKAGE
(TOP VIEW)**



description

This hex inverter contains six independent inverters designed for 1.65-V to 3.6-V V_{CC} operation.

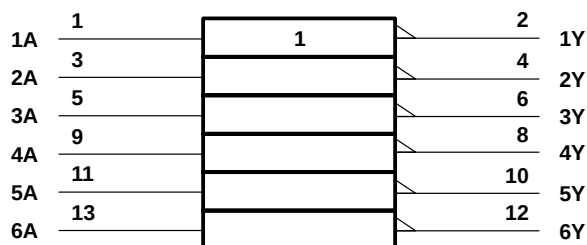
The SN74ALVC04 performs the Boolean function $Y = \bar{A}$.

The SN74ALVC04 is characterized for operation from -40°C to 85°C .

**FUNCTION TABLE
(each inverter)**

INPUT A	OUTPUT Y
H	L
L	H

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram, each inverter (positive logic)



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 **TEXAS
INSTRUMENTS**

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SN74ALVC04

HEX INVERTER

SCES117F – JULY 1997 – REVISED FEBRUARY 1999

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): D package	127°C/W
DGV package	182°C/W
PW package	170°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		5	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	10			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	V _I = V _{CC} or GND	3.3 V	3.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	Y	‡	1	3	3.3		1	2.8	ns

‡ This information was not available at the time of publication.

operating characteristics, T_A = 25°C

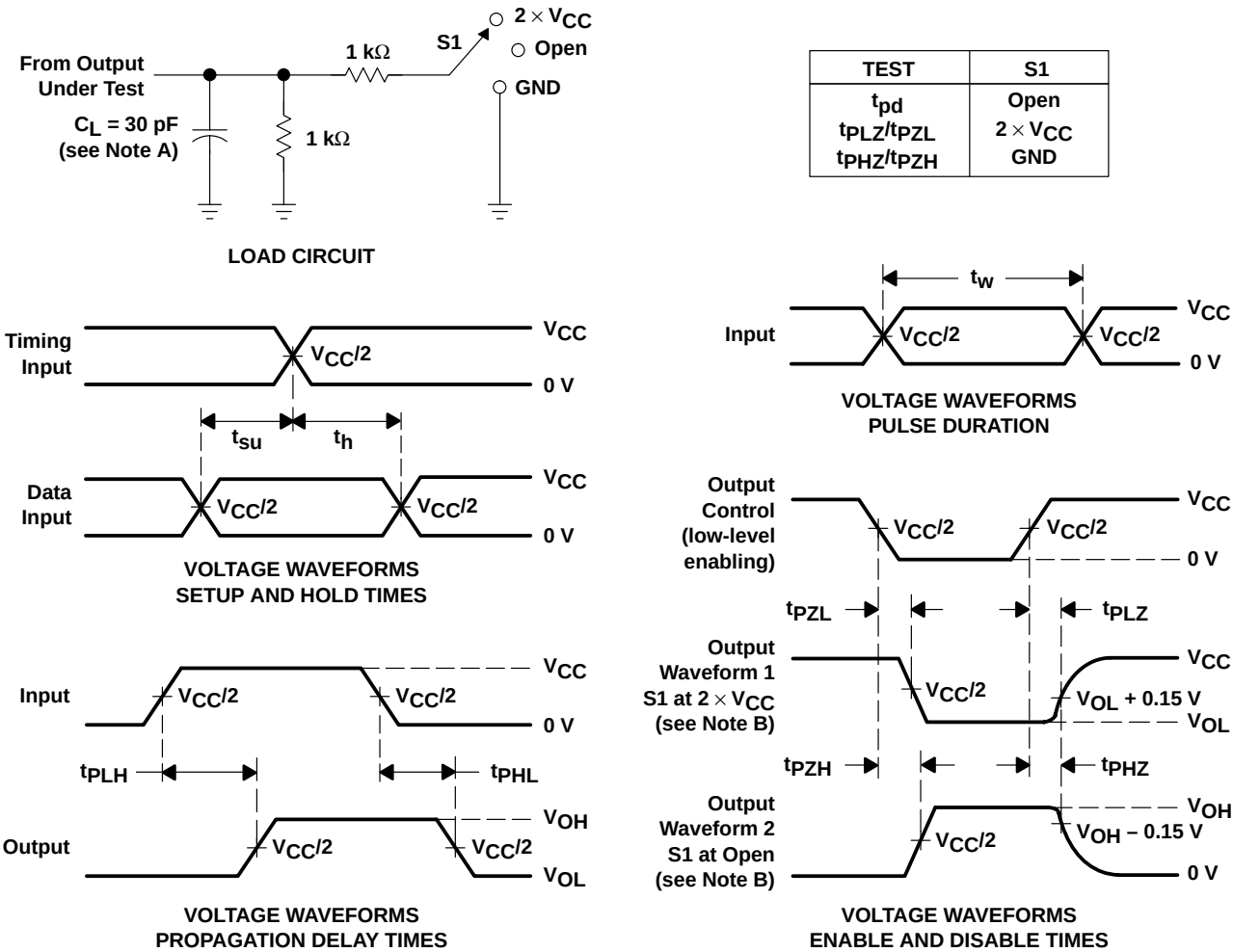
PARAMETER	TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
		TYP	TYP	TYP	
C _{pd} Power dissipation capacitance per inverter	C _L = 0, f = 10 MHz	‡	23	27.5	pF

‡ This information was not available at the time of publication.

SN74ALVC04 HEX INVERTER

SCES117F – JULY 1997 – REVISED FEBRUARY 1999

PARAMETER MEASUREMENT INFORMATION $V_{CC} = 1.8\text{ V}$

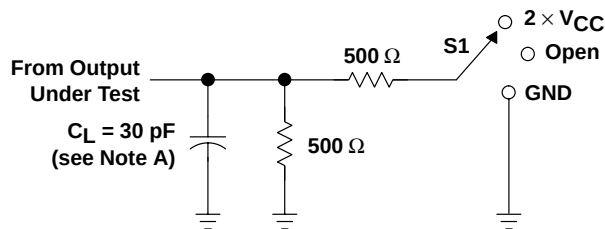


- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

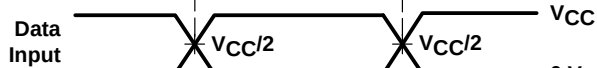
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

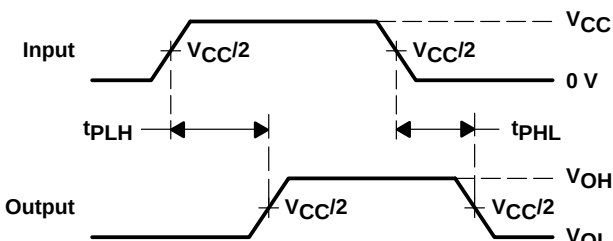


LOAD CIRCUIT

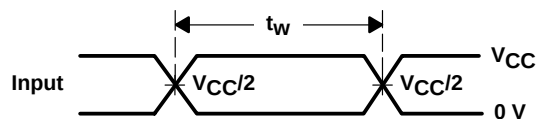
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	$2 \times V_{CC}$
t_{PHZ}/t_{PHZ}	GND



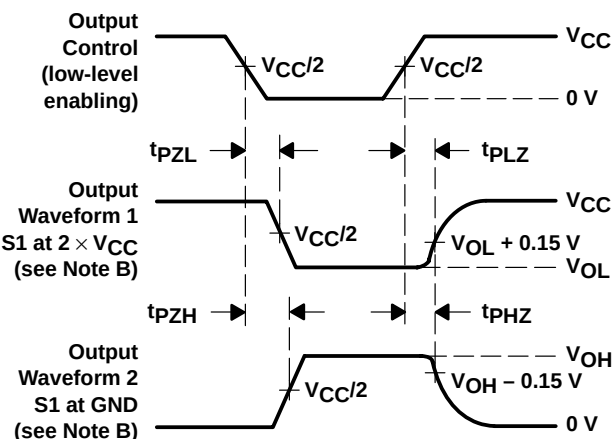
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
D. The outputs are measured one at a time with one transition per measurement.
E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
F. t_{PZL} and t_{PZH} are the same as t_{en} .
G. t_{PLH} and t_{PHL} are the same as t_{pd} .

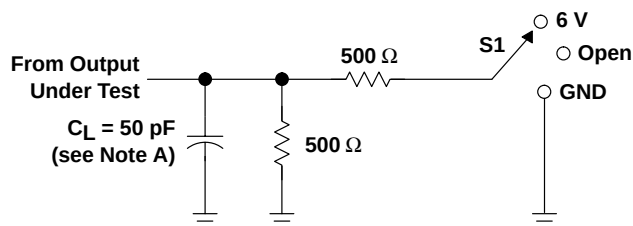
Figure 2. Load Circuit and Voltage Waveforms

SN74ALVC04 HEX INVERTER

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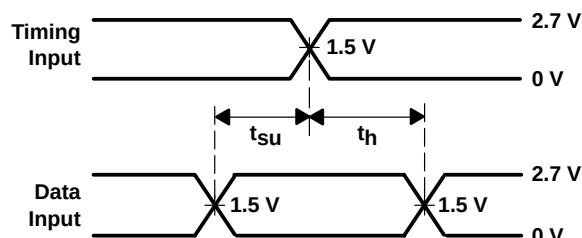
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

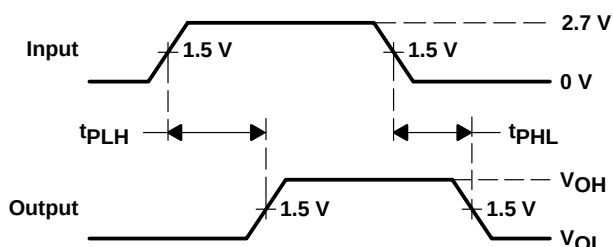


LOAD CIRCUIT

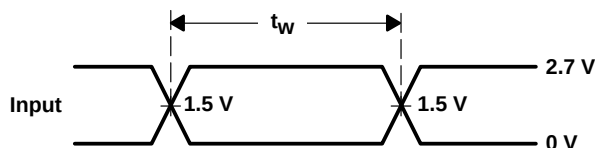
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PHL}	GND



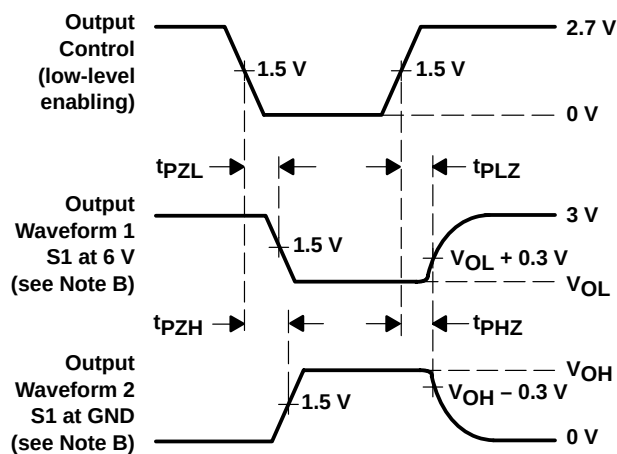
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



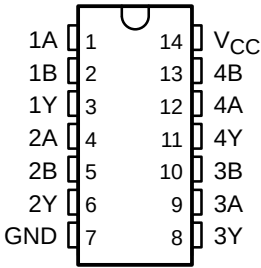
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

- **EPIC™** (Enhanced-Performance Implanted CMOS) Submicron Process
- **ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)**
- **Latch-Up Performance Exceeds 250 mA Per JESD 17**
- **Package Options Include Plastic Small-Outline (D), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages**

D, DGV, OR PW PACKAGE
(TOP VIEW)



description

This quadruple 2-input positive-AND gate is designed for 1.65-V to 3.6-V V_{CC} operation.

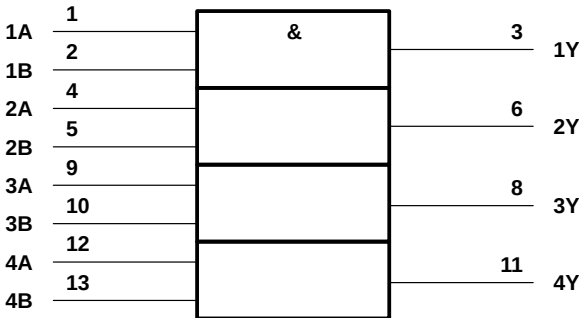
The device performs the Boolean function $Y = A \bullet B$ or $Y = \overline{\overline{A} + \overline{B}}$ in positive logic.

The SN74ALVC08 is characterized for operation from -40°C to 85°C .

FUNCTION TABLE
(each gate)

INPUTS		OUTPUT
A	B	Y
H	H	H
L	X	L
X	L	L

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram, each gate (positive logic)



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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SN74ALVC08

QUADRUPLE 2-INPUT POSITIVE-AND GATE

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): D package	127°C/W
DGV package	182°C/W
PW package	170°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate	0	5	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



SN74ALVC08

QUADRUPLE 2-INPUT POSITIVE-AND GATE

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	10			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	V _I = V _{CC} or GND	3.3 V	4.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V ± 0.15 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A or B	Y	1.2	5.3	1	3.2	3		1.2	2.9	ns

operating characteristics, T_A = 25°C

PARAMETER	TEST CONDITIONS	V _{CC} = 1.8 V ± 0.15 V	V _{CC} = 2.5 V ± 0.2 V	V _{CC} = 3.3 V ± 0.3 V	UNIT
		TYP	TYP	TYP	
C _{pd} Power dissipation capacitance per gate	C _L = 0, f = 10 MHz	24	25	26	pF



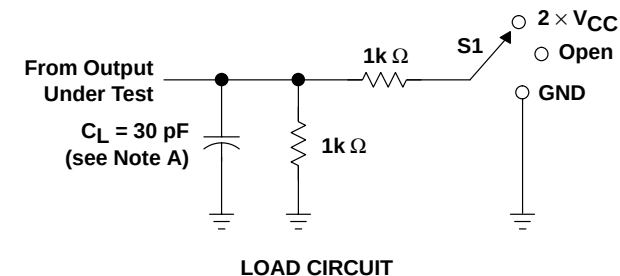
SN74ALVC08

QUADRUPLE 2-INPUT POSITIVE-AND GATE

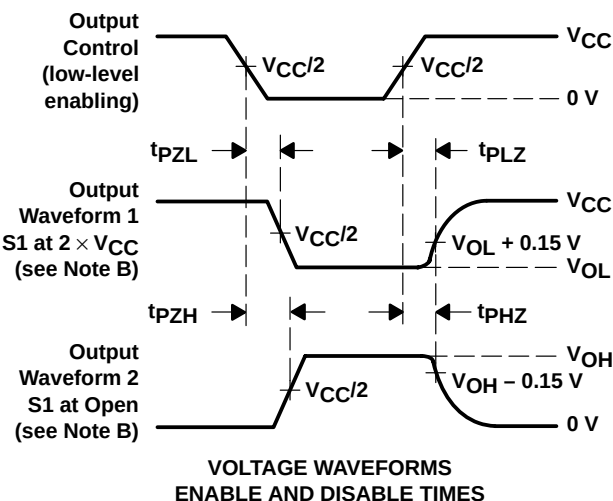
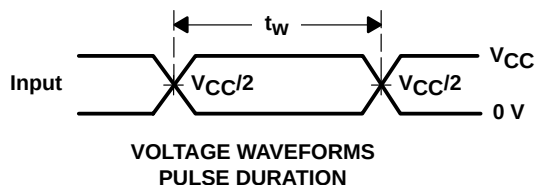
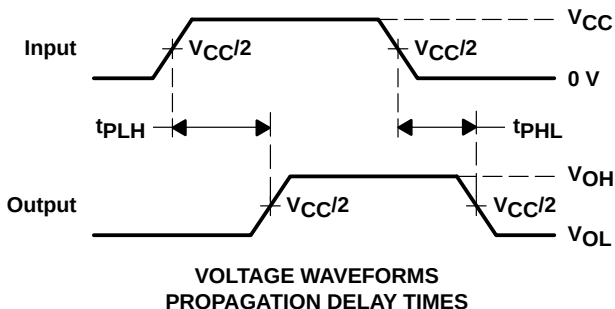
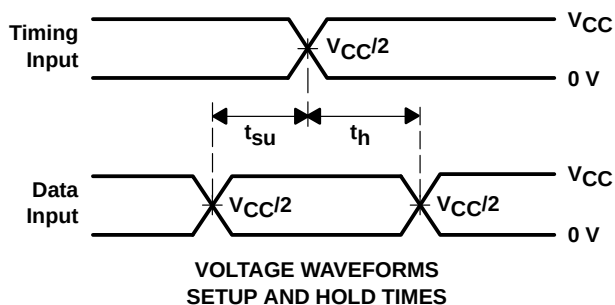
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PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}$$



TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	Open

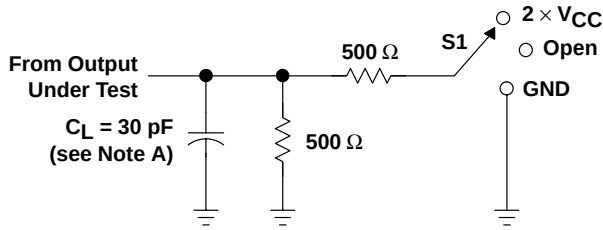


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

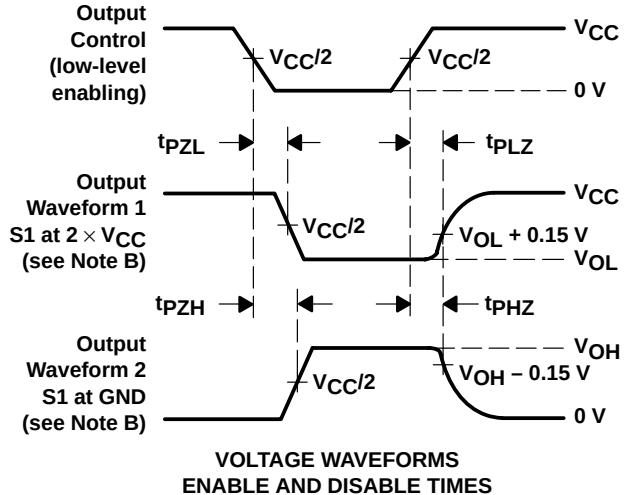
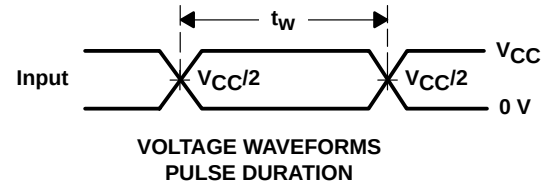
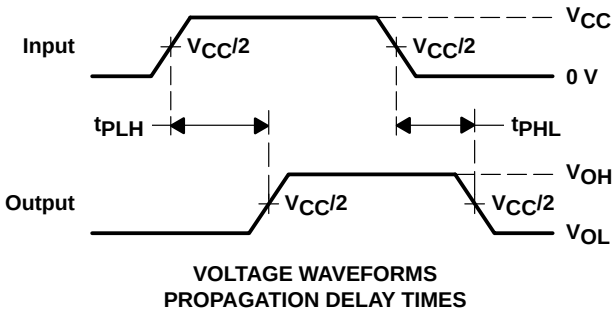
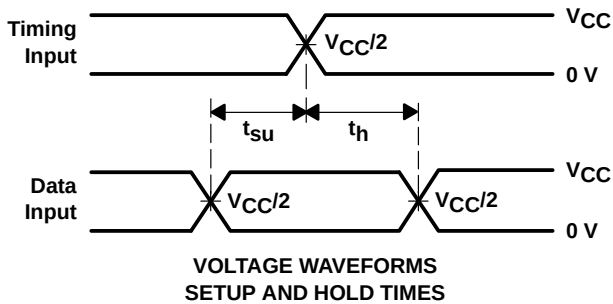
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

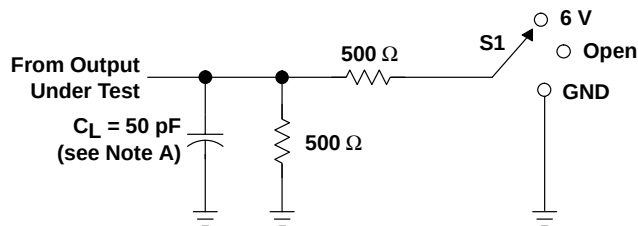
SN74ALVC08

QUADRUPLE 2-INPUT POSITIVE-AND GATE

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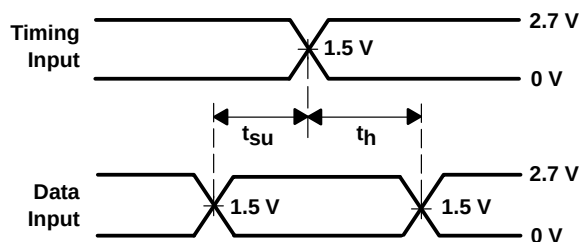
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$

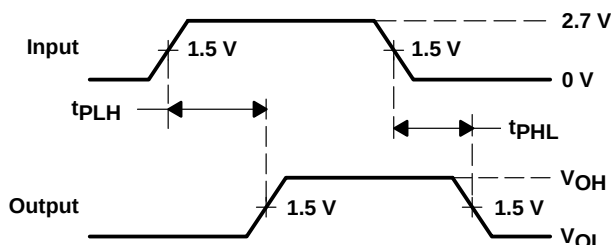


LOAD CIRCUIT

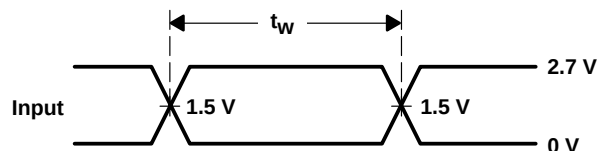
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



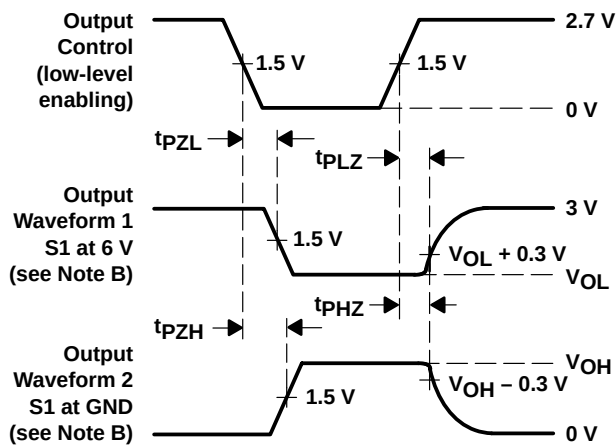
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

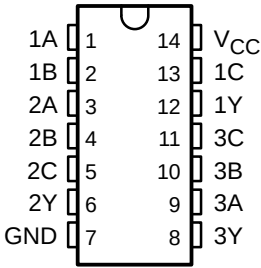
SN74ALVC10

TRIPLE 3-INPUT POSITIVE-NAND GATE

SCES106D – JULY 1997 – REVISED OCTOBER 1998

- **EPIC™** (Enhanced-Performance Implanted CMOS) Submicron Process
- **ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)**
- **Latch-Up Performance Exceeds 250 mA Per JESD 17**
- **Package Options Include Plastic Small-Outline (D), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages**

**D, DGV, OR PW PACKAGE
(TOP VIEW)**



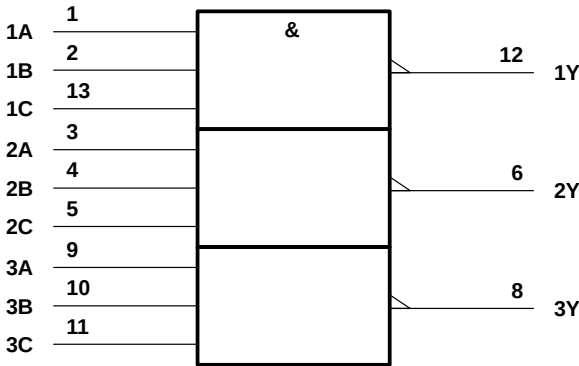
description

This triple 3-input positive-NAND gate is designed for 1.65-V to 3.6-V V_{CC} operation.
 The SN74ALVC10 performs the Boolean function $Y = \overline{A \cdot B \cdot C}$ or $Y = \overline{A} + \overline{B} + \overline{C}$ in positive logic.
 The SN74ALVC10 is characterized for operation from -40°C to 85°C .

**FUNCTION TABLE
(each gate)**

INPUTS			OUTPUT Y
A	B	C	
H	H	H	L
L	X	X	H
X	L	X	H
X	X	L	H

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



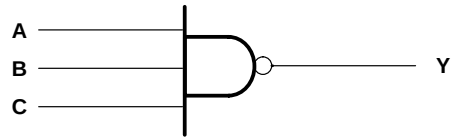
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SN74ALVC10
TRIPLE 3-INPUT POSITIVE-NAND GATE

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logic diagram, each gate (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): D package	127°C/W
DGV package	182°C/W
PW package	170°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate	0	5	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

SN74ALVC10

TRIPLE 3-INPUT POSITIVE-NAND GATE

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	10			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	V _I = V _{CC} or GND	3.3 V	4			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V ± 0.15 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A, B, or C	Y	1.1	4.8	1	3	3.3		1	3	ns

operating characteristics, T_A = 25°C

PARAMETER	TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
		TYP	TYP	TYP	
C _{pd} Power dissipation capacitance per gate	C _L = 0, f = 10 MHz	23	24	26	pF



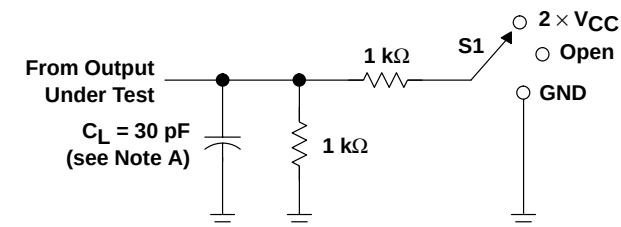
SN74ALVC10

TRIPLE 3-INPUT POSITIVE-NAND GATE

SCES106D – JULY 1997 – REVISED OCTOBER 1998

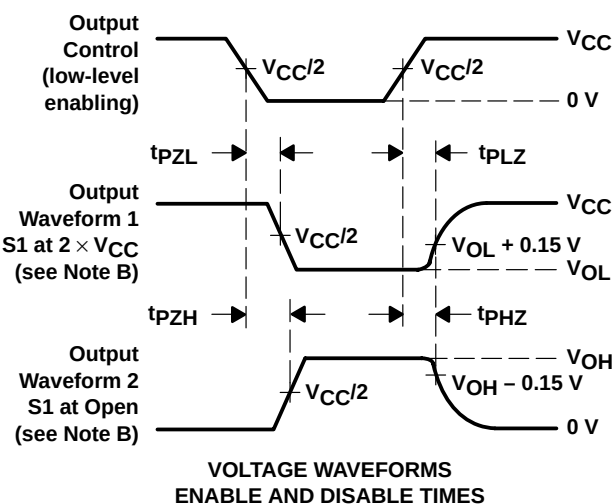
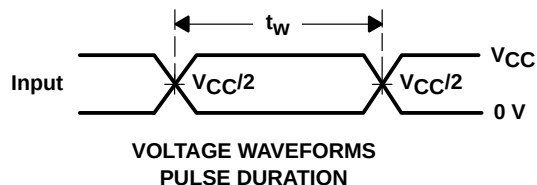
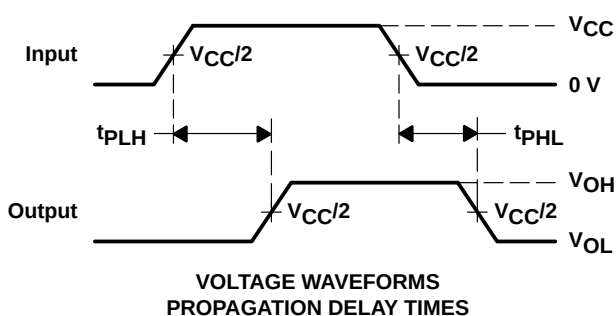
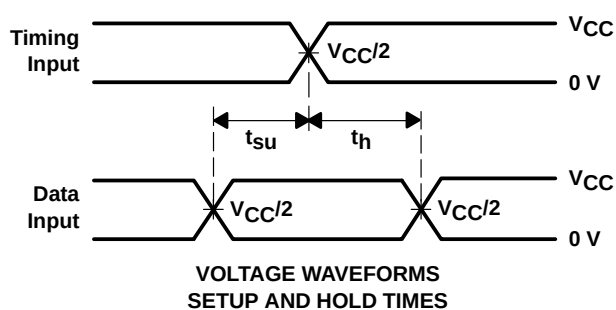
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}$$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PHL}	Open

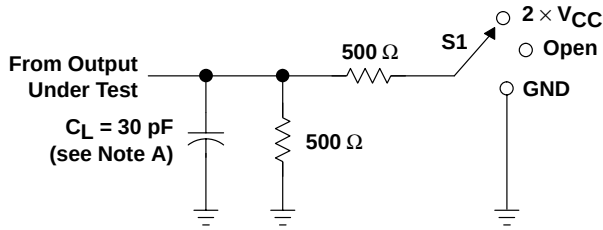


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

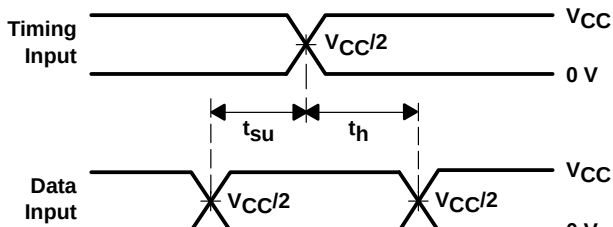
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

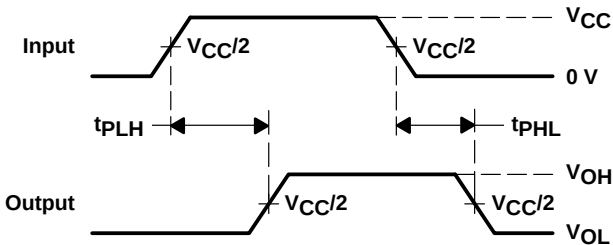


LOAD CIRCUIT

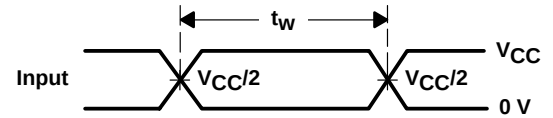
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



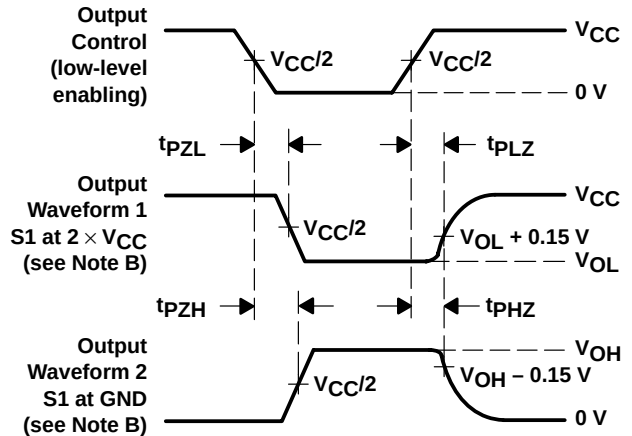
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

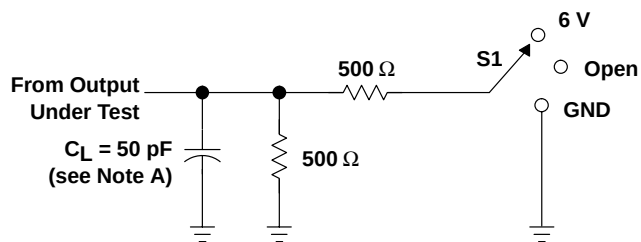
SN74ALVC10

TRIPLE 3-INPUT POSITIVE-NAND GATE

SCES106D – JULY 1997 – REVISED OCTOBER 1998

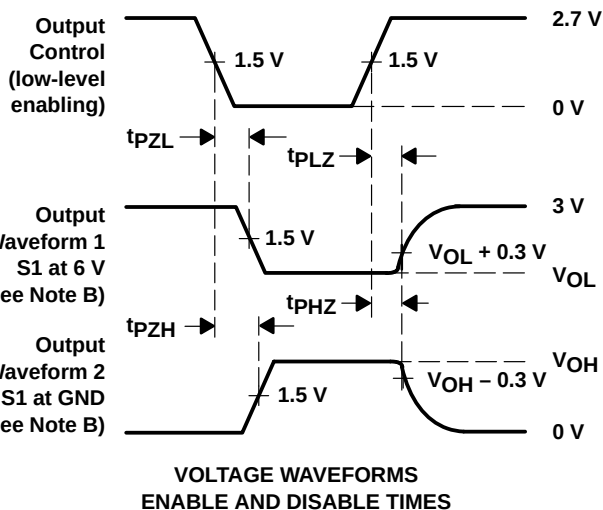
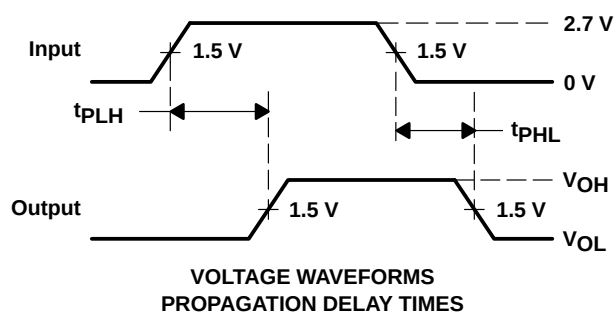
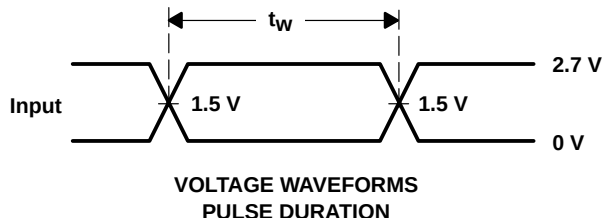
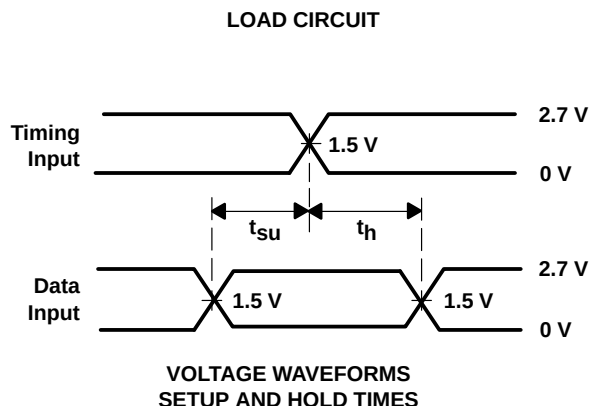
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVC14 HEX SCHMITT-TRIGGER INVERTER

SCES107D – JULY 1997 – REVISED JANUARY 1999

- **EPIC™** (Enhanced-Performance Implanted CMOS) Submicron Process
- Package Options Include Plastic Small-Outline (D), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages

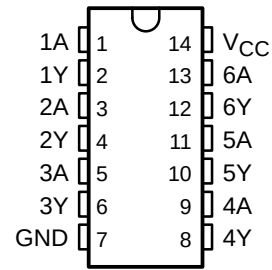
description

This hex Schmitt-trigger inverter is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVC14 contains six independent inverters, and performs the Boolean function $Y = \bar{A}$.

The SN74ALVC14 is characterized for operation from -40°C to 85°C .

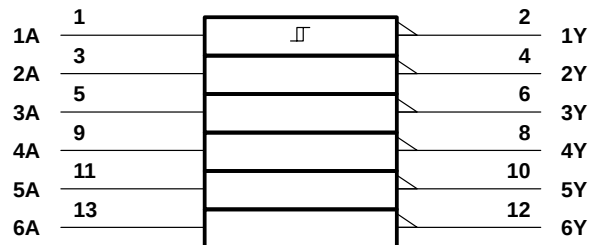
D, DGV, OR PW PACKAGE
(TOP VIEW)



FUNCTION TABLE
(each gate)

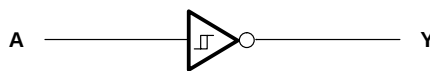
INPUT A	OUTPUT Y
H	L
L	H

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram, each inverter (positive logic)



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PRODUCT PREVIEW

SN74ALVC14

HEX SCHMITT-TRIGGER INVERTER

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 6.5 V
Input voltage range, V_I (see Note 1)	–0.5 V to 6.5 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): D package	127°C/W
DGV package	182°C/W
PW package	170°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

PRODUCT PREVIEW



SN74ALVC14 HEX SCHMITT-TRIGGER INVERTER

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{T+} Positive-going threshold		1.65 V				V
		2.7 V	0.8		2	
		3 V	0.8		2	
		3.6 V	0.8		2	
V _{T–} Negative-going threshold		1.65 V				V
		2.7 V	0.4		1.4	
		3 V	0.6		1.5	
		3.6 V	0.8		1.8	
ΔV _T Hysteresis (V _{T+} – V _{T–})		1.65 V				V
		2.7 V	0.3		1.1	
		3 V	0.3		1.2	
		3.6 V	0.3		1.2	
V _{OH}	I _{OH} = –100 μA	1.65 V to 3.6 V	V _{CC} – 0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 μA	1.65 V to 3.6 V			0.2	V
	I _{OL} = 4 mA	1.65 V			0.45	
	I _{OL} = 6 mA	2.3 V			0.4	
	I _{OL} = 12 mA	2.3 V			0.7	
		2.7 V			0.4	
	I _{OL} = 24 mA	3 V			0.55	
I _I	V _I = V _{CC} or GND	3.6 V			±5	μA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V			20	μA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V			750	μA
C _i	V _I = V _{CC} or GND	3.3 V				pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	Y								ns

operating characteristics, T_A = 25°C

PARAMETER	TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
		TYP	TYP	TYP	
C _{pd} Power dissipation capacitance per inverter	C _L = 0, f = 10 MHz				pF

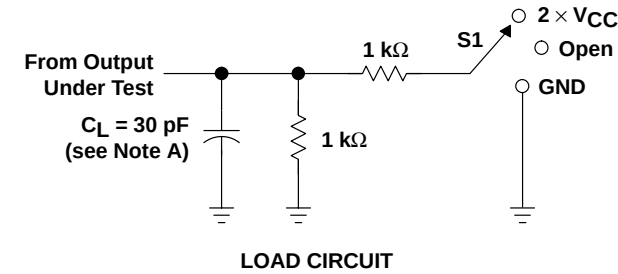
PRODUCT PREVIEW



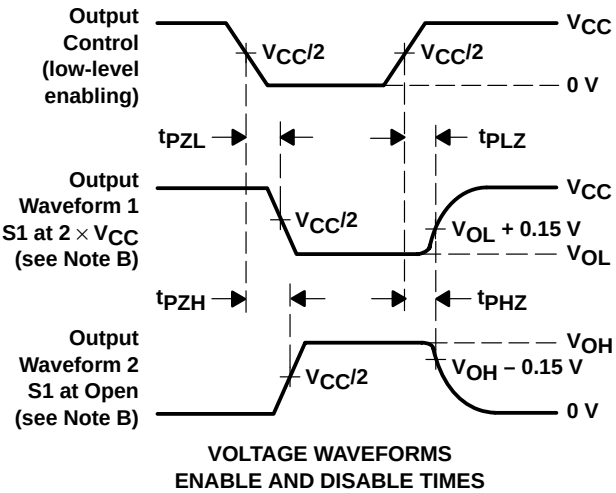
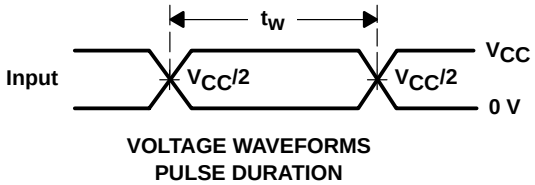
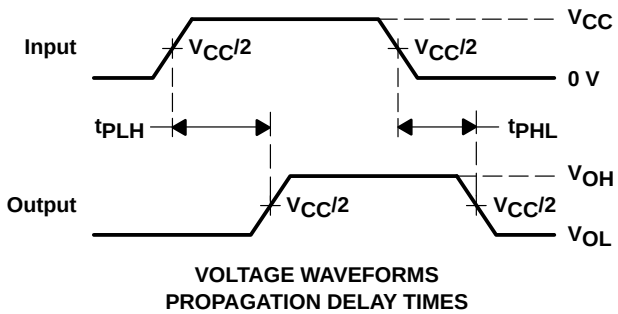
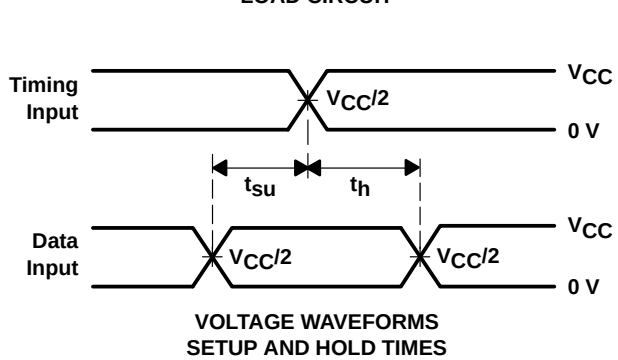
SN74ALVC14 HEX SCHMITT-TRIGGER INVERTER

SCES107D – JULY 1997 – REVISED JANUARY 1999

PARAMETER MEASUREMENT INFORMATION $V_{CC} = 1.8\text{ V}$



TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PHL}	GND

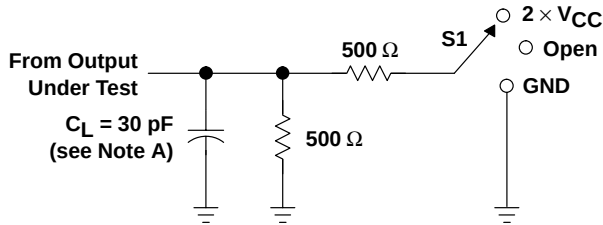


- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

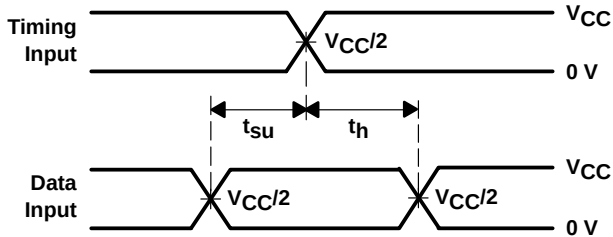
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

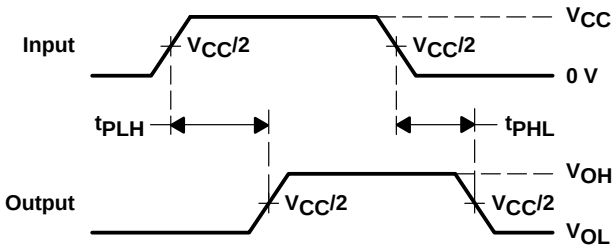


LOAD CIRCUIT

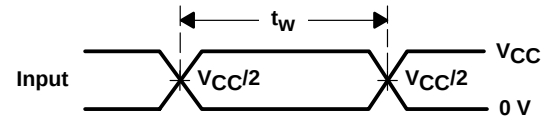
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



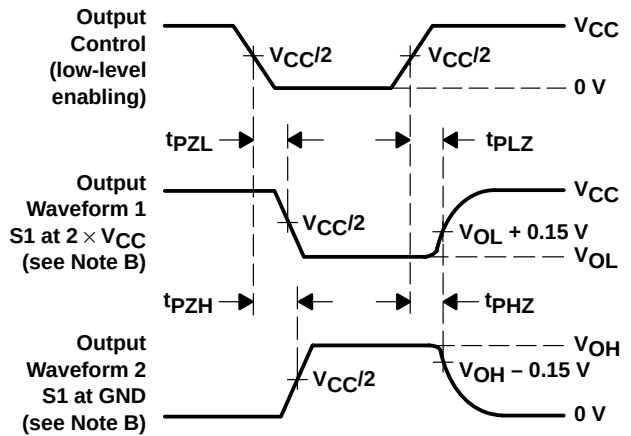
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

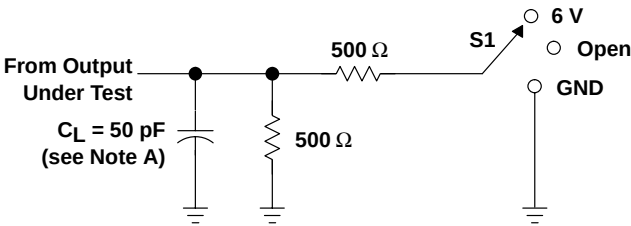
- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
D. The outputs are measured one at a time with one transition per measurement.
E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
F. t_{PZL} and t_{PZH} are the same as t_{en} .
G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVC14 HEX SCHMITT-TRIGGER INVERTER

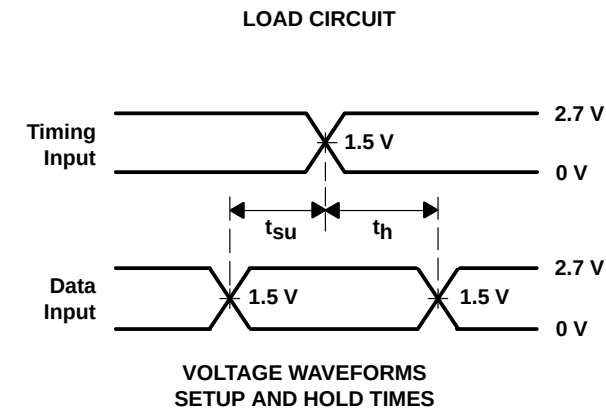
SCES107D – JULY 1997 – REVISED JANUARY 1999

PARAMETER MEASUREMENT INFORMATION $V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

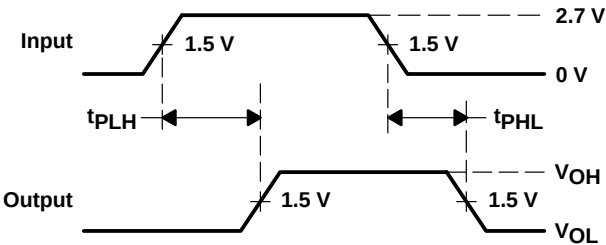


LOAD CIRCUIT

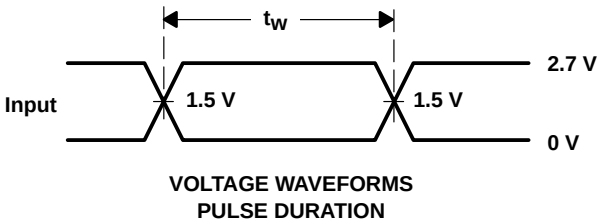
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



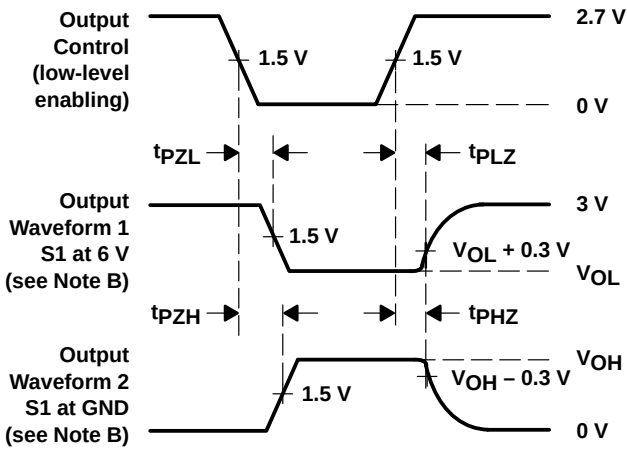
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
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 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

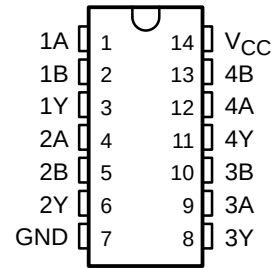
Figure 3. Load Circuit and Voltage Waveforms

SN74ALVC32 QUADRUPLE 2-INPUT POSITIVE-OR GATE

SCES108D – JULY 1997 – REVISED AUGUST 1998

- **EPIC™** (Enhanced-Performance Implanted CMOS) Submicron Process
- **ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)**
- **Latch-Up Performance Exceeds 250 mA Per JESD 17**
- **Package Options Include Plastic Small-Outline (D), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages**

**D, DGV, OR PW PACKAGE
(TOP VIEW)**



description

This quadruple 2-input positive-OR gate is designed for 1.65-V to 3.6-V V_{CC} operation.

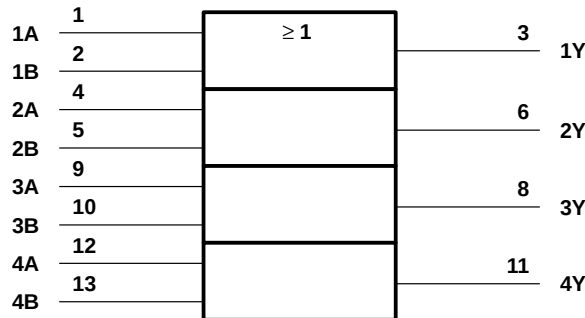
The SN74ALVC32 performs the Boolean function $Y = \overline{A} \cdot \overline{B}$ or $Y = A + B$ in positive logic.

The SN74ALVC32 is characterized for operation from –40°C to 85°C.

**FUNCTION TABLE
(each gate)**

INPUTS		OUTPUT Y
A	B	
H	X	H
X	H	H
L	L	L

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram, each gate (positive logic)



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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SN74ALVC32

QUADRUPLE 2-INPUT POSITIVE-OR GATE

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): D package	127°C/W
DGV package	182°C/W
PW package	170°C/W

Storage temperature range, T_{stg} –65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate	0	5	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

SN74ALVC32

QUADRUPLE 2-INPUT POSITIVE-OR GATE

SCES108D – JULY 1997 – REVISED AUGUST 1998

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	10			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	V _I = V _{CC} or GND	3.3 V	4			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V ± 0.15 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A or B	Y	1	4.7	1	3.1	2.9		1	2.8	ns

operating characteristics, T_A = 25°C

PARAMETER	TEST CONDITIONS	V _{CC} = 1.8 V ± 0.15 V	V _{CC} = 2.5 V ± 0.2 V	V _{CC} = 3.3 V ± 0.3 V	UNIT
		TYP	TYP	TYP	
C _{pd} Power dissipation capacitance per gate	C _L = 0, f = 10 MHz	23	24	26	pF



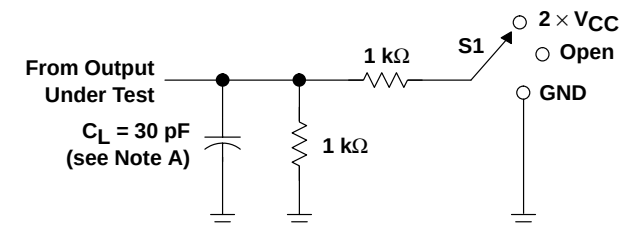
SN74ALVC32

QUADRUPLE 2-INPUT POSITIVE-OR GATE

SCES108D – JULY 1997 – REVISED AUGUST 1998

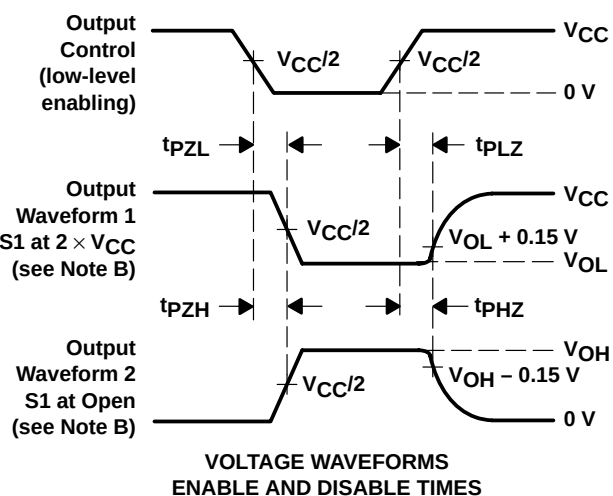
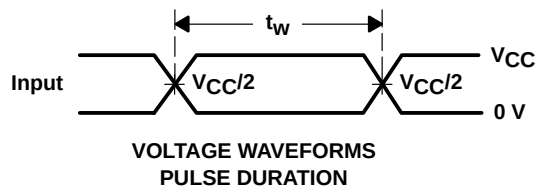
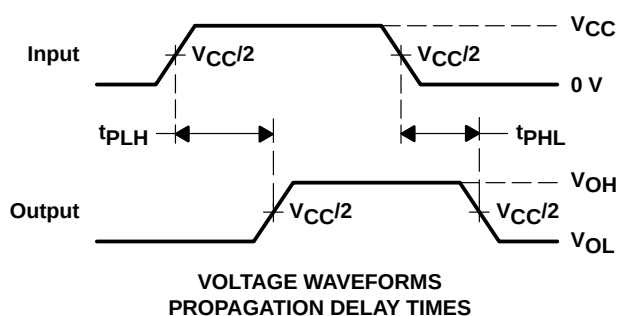
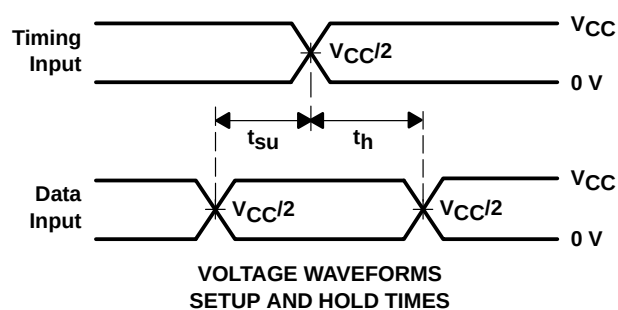
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}$$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	$2 \times V_{CC}$
t_{PHZ}/t_{PHL}	Open

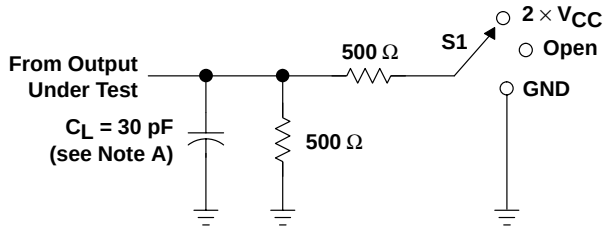


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

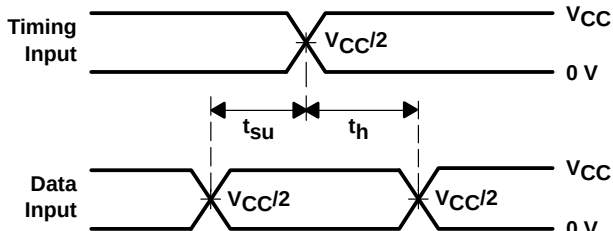
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

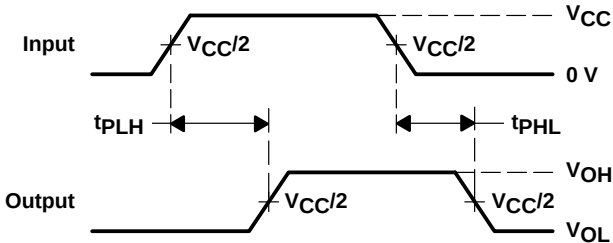


LOAD CIRCUIT

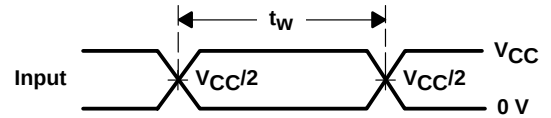
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



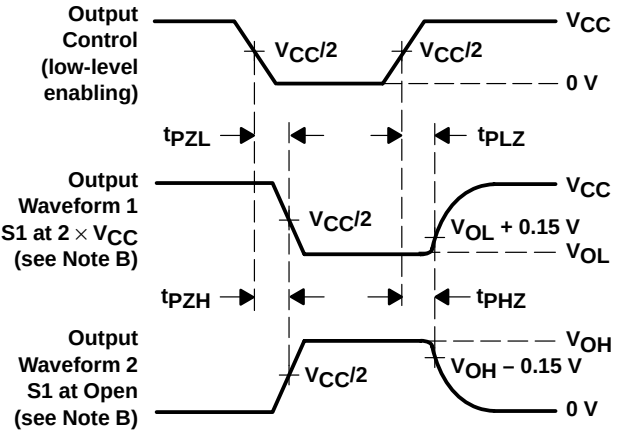
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES: A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
- D. The outputs are measured one at a time with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

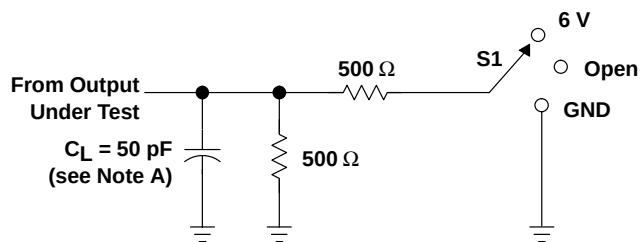
SN74ALVC32

QUADRUPLE 2-INPUT POSITIVE-OR GATE

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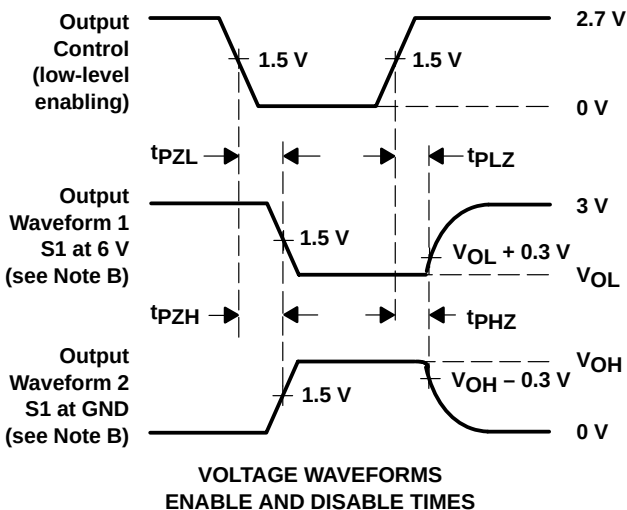
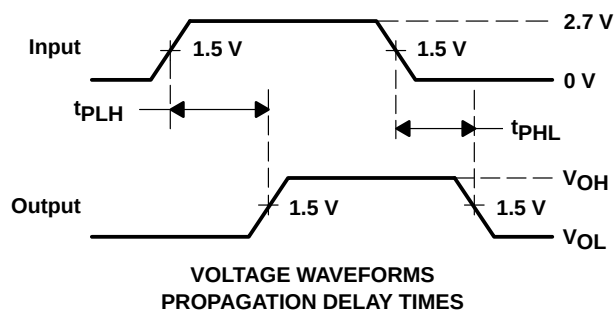
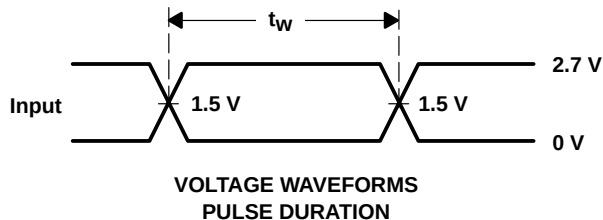
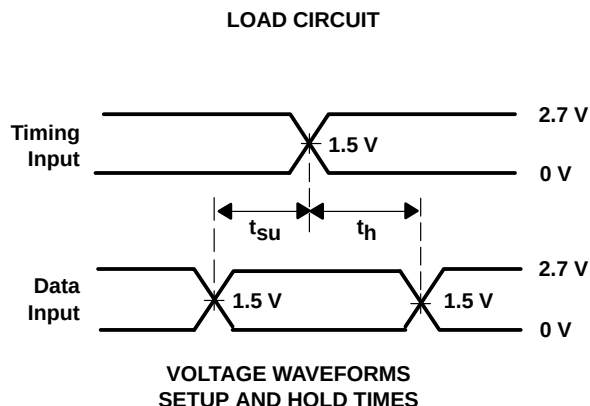
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVC74

DUAL POSITIVE-EDGE-TRIGGERED D-TYPE FLIP-FLOP WITH CLEAR AND PRESET

SCES109E – JULY 1997 – REVISED JANUARY 1999

- **EPIC™** (Enhanced-Performance Implanted CMOS) Submicron Process
- Package Options Include Plastic Small-Outline (D), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages

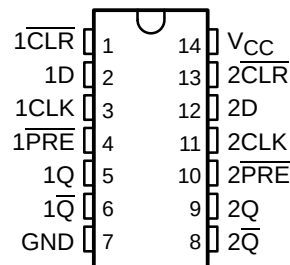
description

This dual positive-edge-triggered D-type flip-flop is designed for 1.65-V to 3.6-V V_{CC} operation.

A low level at the preset ($\overline{PRE}$) or clear ($\overline{CLR}$) inputs sets or resets the outputs, regardless of the levels of the other inputs. When $\overline{PRE}$ and $\overline{CLR}$ are inactive (high), data at the data (D) input meeting the setup time requirements is transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold-time interval, data at the D input may be changed without affecting the levels at the outputs.

The SN74ALVC74 is characterized for operation from -40°C to 85°C .

D, DGV, OR PW PACKAGE
(TOP VIEW)

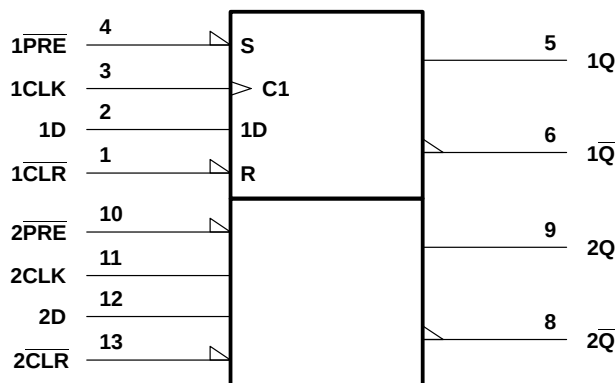


FUNCTION TABLE

INPUTS				OUTPUTS	
PRE	CLR	CLK	D	Q	$\overline{Q}$
L	H	X	X	H	L
H	L	X	X	L	H
L	L	X	X	H [†]	H [†]
H	H	↑	H	H	L
H	H	↑	L	L	H
H	H	L	X	Q ₀	$\overline{Q}_0$

[†] This configuration is unstable; that is, it does not persist when $\overline{PRE}$ or $\overline{CLR}$ returns to its inactive (high) level.

logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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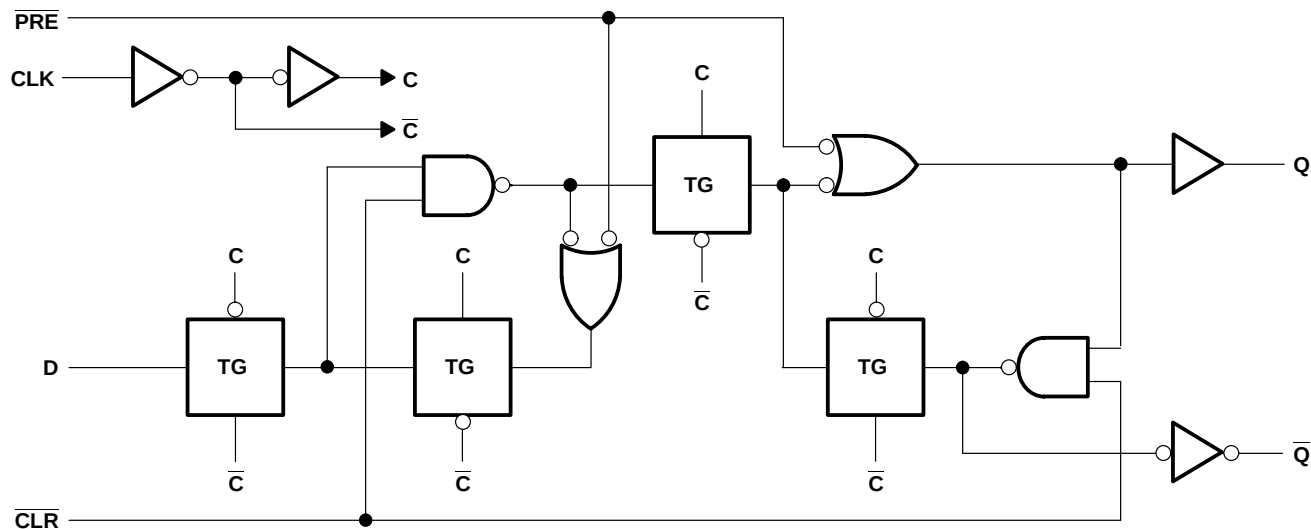
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SN74ALVC74

DUAL POSITIVE-EDGE-TRIGGERED D-TYPE FLIP-FLOP WITH CLEAR AND PRESET

SCES109E – JULY 1997 – REVISED JANUARY 1999

logic diagram, each flip-flop (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): D package	127°C/W
DGV package	182°C/W
PW package	170°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

SN74ALVC74

DUAL POSITIVE-EDGE-TRIGGERED D-TYPE FLIP-FLOP WITH CLEAR AND PRESET

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V _{CC}	Supply voltage	1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}	V
		V _{CC} = 2.3 V to 2.7 V	1.7	
		V _{CC} = 2.7 V to 3.6 V	2	
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}	V
		V _{CC} = 2.3 V to 2.7 V	0.7	
		V _{CC} = 2.7 V to 3.6 V	0.8	
V _I	Input voltage	0	V _{CC}	V
V _O	Output voltage	0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	–4	mA
		V _{CC} = 2.3 V	–12	
		V _{CC} = 2.7 V	–12	
		V _{CC} = 3 V	–24	
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4	mA
		V _{CC} = 2.3 V	12	
		V _{CC} = 2.7 V	12	
		V _{CC} = 3 V	24	
Δt/Δv	Input transition rise or fall rate		10	ns/V
T _A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP†	MAX	UNIT
V _{OH}	I _{OH} = –100 μA	1.65 V to 3.6 V	V _{CC} –0.2		V	
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 μA	1.65 V to 3.6 V	0.2		V	
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5		μA	
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	20		μA	
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750		μA	
C _i	V _I = V _{CC} or GND	3.3 V			pF	

† All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

PRODUCT PREVIEW



SN74ALVC74

DUAL POSITIVE-EDGE-TRIGGERED D-TYPE FLIP-FLOP WITH CLEAR AND PRESET

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency										MHz
t _w	Pulse duration	PRE or CLR low									ns
		CLK high or low									
t _{su}	Setup time	Data before CLK↑									ns
		PRE or CLR inactive									
t _h	Hold time										ns

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP		MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}											MHz
t _{pd}	CLK	Q or $\overline{Q}$									ns
	PRE or CLR										

operating characteristics, T_A = 25°C

PARAMETER	TEST CONDITIONS	V _{CC} = 1.8V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
		TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance per flip-flop C _L = 0, f = 10 MHz				pF

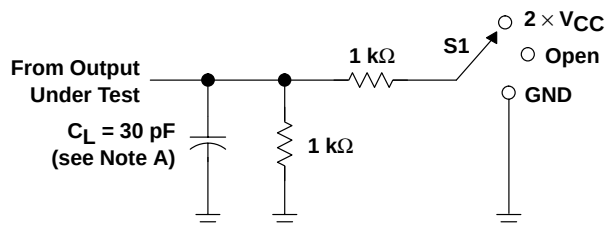
SN74ALVC74

DUAL POSITIVE-EDGE-TRIGGERED D-TYPE FLIP-FLOP WITH CLEAR AND PRESET

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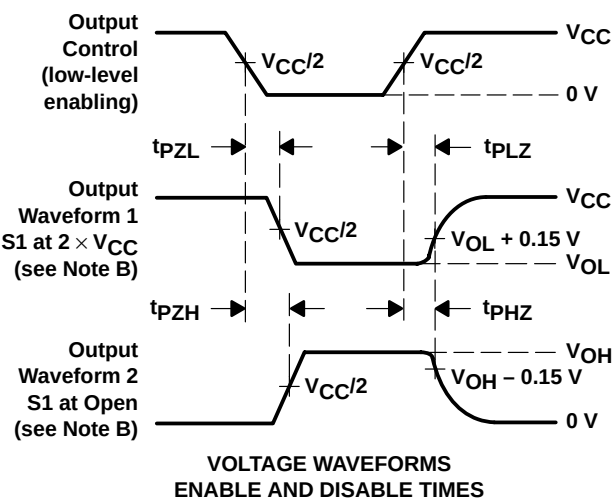
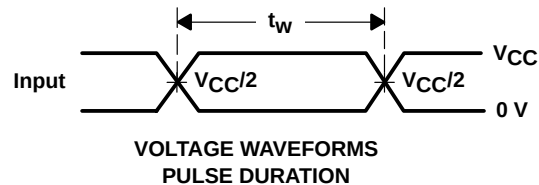
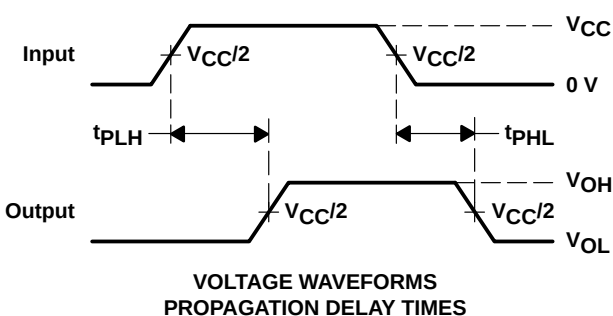
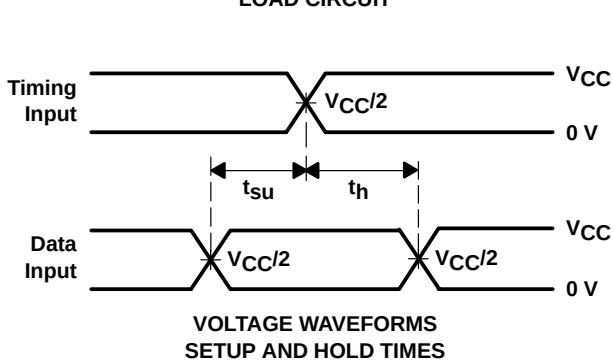
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

PRODUCT PREVIEW

SN74ALVC74

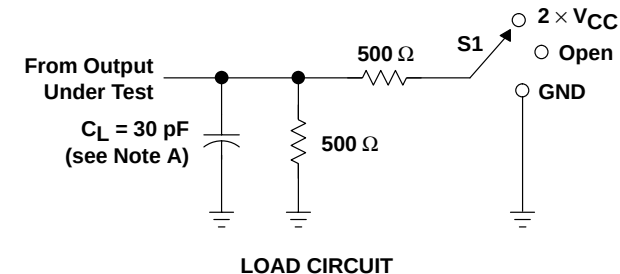
DUAL POSITIVE-EDGE-TRIGGERED D-TYPE FLIP-FLOP

WITH CLEAR AND PRESET

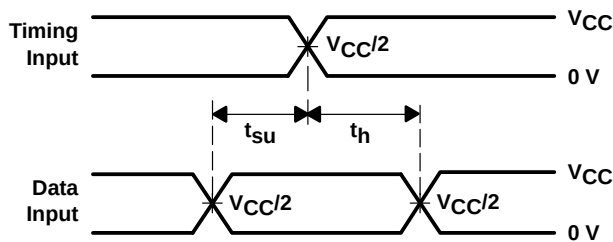
SCES109E – JULY 1997 – REVISED JANUARY 1999

PARAMETER MEASUREMENT INFORMATION

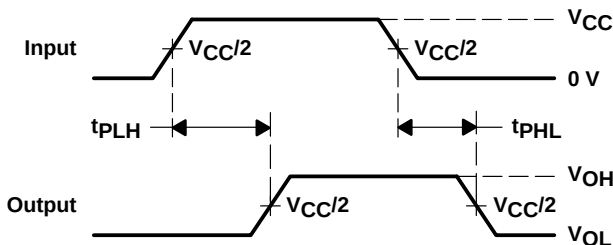
$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$



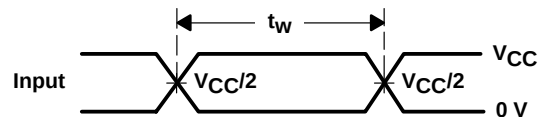
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



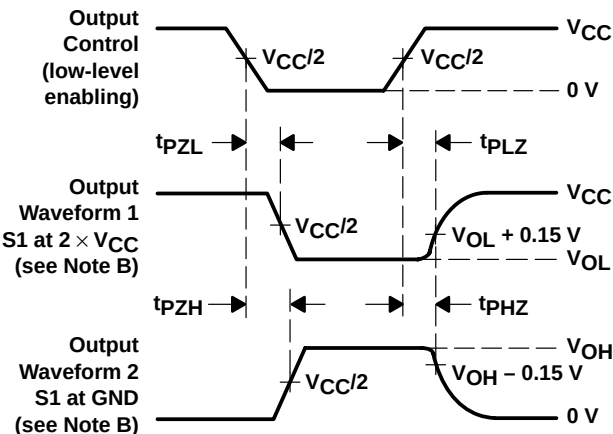
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

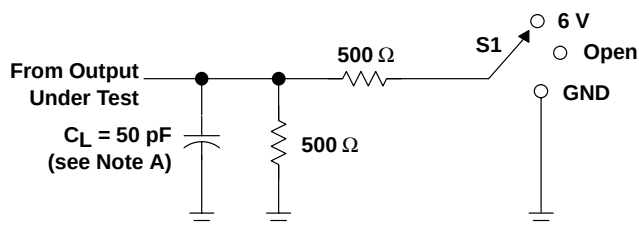
SN74ALVC74

DUAL POSITIVE-EDGE-TRIGGERED D-TYPE FLIP-FLOP WITH CLEAR AND PRESET

SCES109E – JULY 1997 – REVISED JANUARY 1999

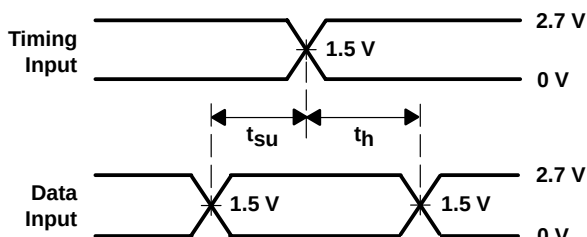
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V}$ AND $3.3 \text{ V} \pm 0.3 \text{ V}$

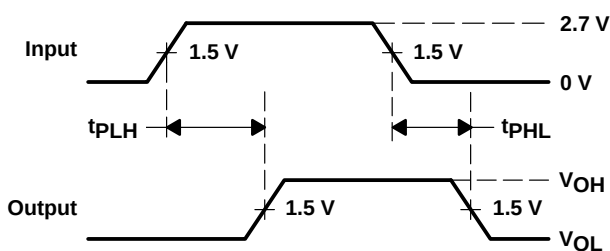


LOAD CIRCUIT

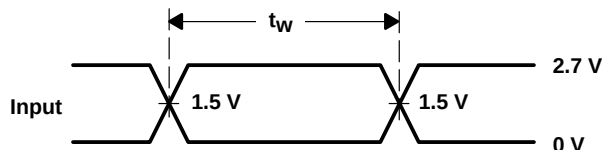
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



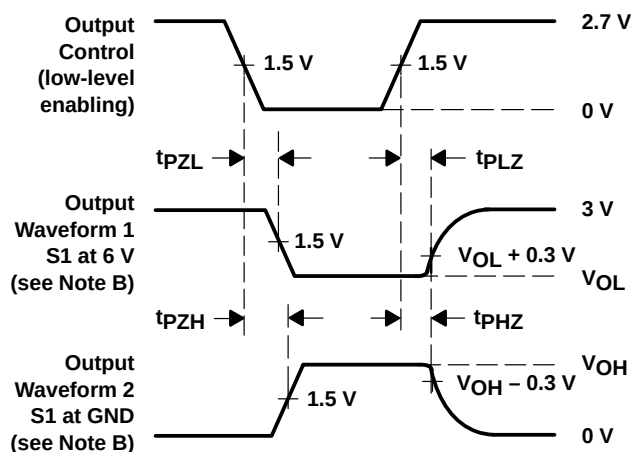
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

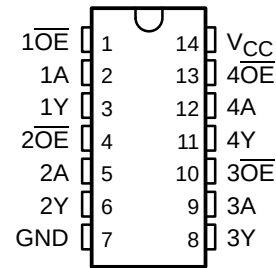
Figure 3. Load Circuit and Voltage Waveforms

SN74ALVC125 QUADRUPLE BUS BUFFER GATE WITH 3-STATE OUTPUTS

SCES110D – JULY 1997 – REVISED DECEMBER 1998

- **EPIC™** (Enhanced-Performance Implanted CMOS) Submicron Process
- **ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)**
- **Latch-Up Performance Exceeds 250 mA Per JESD 17**
- **Package Options Include Plastic Small-Outline (D), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages**

**D, DGV, OR PW PACKAGE
(TOP VIEW)**



description

This quadruple bus buffer gate is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVC125 features independent line drivers with 3-state outputs. Each output is disabled when the associated output-enable ($\overline{OE}$) input is high.

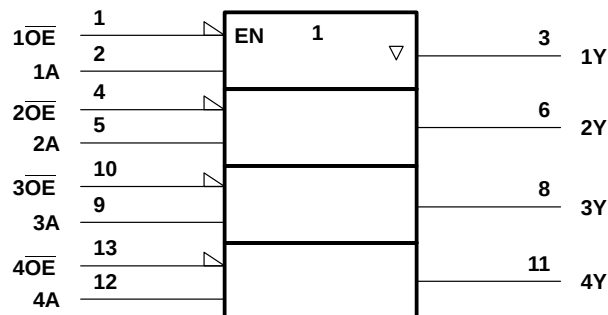
To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74ALVC125 is characterized for operation from -40°C to 85°C .

**FUNCTION TABLE
(each buffer)**

INPUTS		OUTPUT
$\overline{OE}$	A	Y
L	H	H
L	L	L
H	X	Z

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

EPIC is a trademark of Texas Instruments Incorporated.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



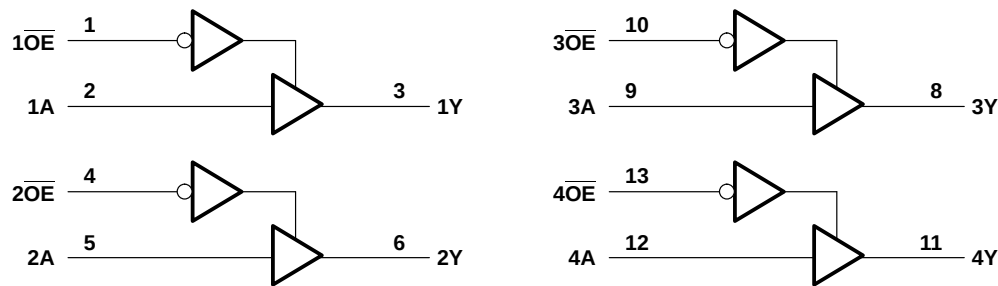
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SN74ALVC125
QUADRUPLE BUS BUFFER GATE
WITH 3-STATE OUTPUTS

SCES110D – JULY 1997 – REVISED DECEMBER 1998

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3):	
D package	127°C/W
DGV package	182°C/W
PW package	170°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

SN74ALVC125
QUADRUPLE BUS BUFFER GATE
WITH 3-STATE OUTPUTS

SCES110D – JULY 1997 – REVISED DECEMBER 1998

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

SN74ALVC125

QUADRUPLE BUS BUFFER GATE

WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
		I _{OL} = 12 mA	2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	10			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3.5			pF
	Data inputs			3.5			
C _o	Outputs	V _O = V _{CC} or GND	3.3 V	5.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

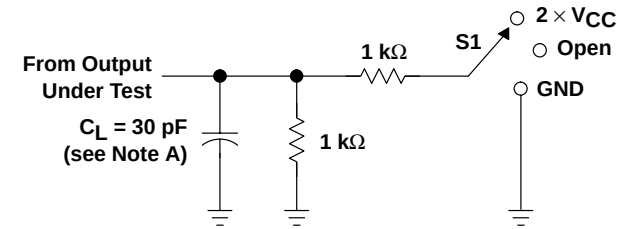
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V ± 0.15 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	Y	1.3	5.3	1	3.2	3.1		1.1	2.8	ns
t _{en}	$\overline{OE}$	Y	1.4	6.4	1	4.1	4.3		1	3.5	ns
t _{dis}	$\overline{OE}$	Y	1.8	5.9	1	3.4	4		1.4	4	ns

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance per gate	Outputs enabled	C _L = 0, f = 10 MHz	15	17	19	pF
		Outputs disabled		2	2	3	

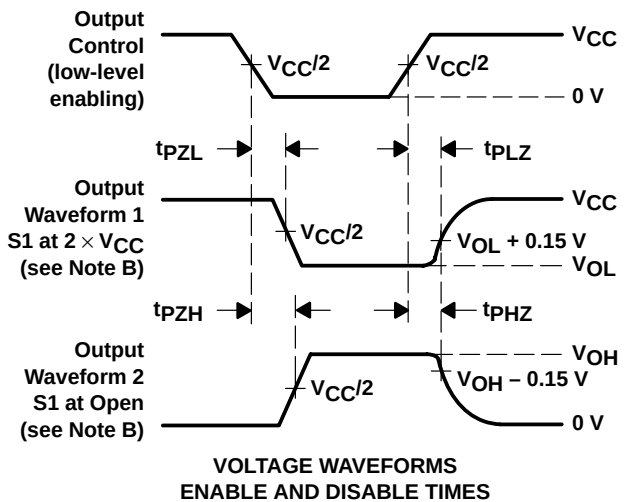
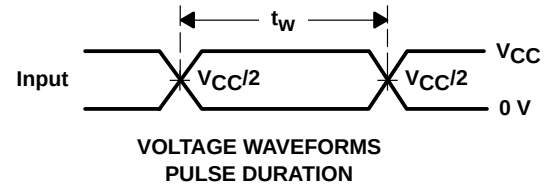
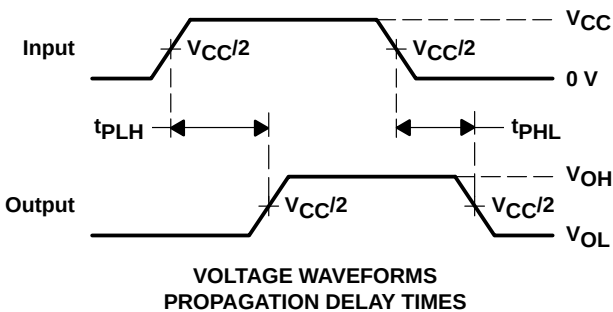
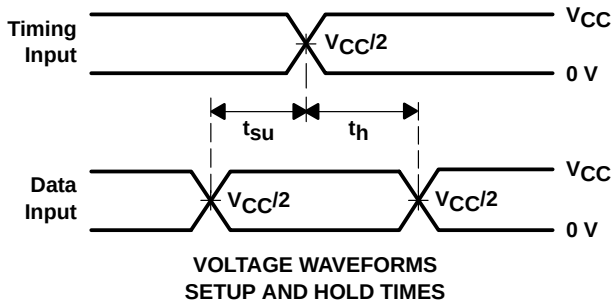


PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR $\leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVC125

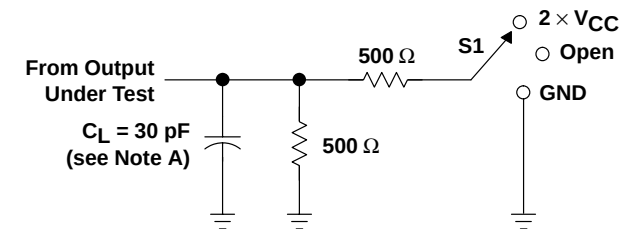
QUADRUPLE BUS BUFFER GATE

WITH 3-STATE OUTPUTS

SCES110D – JULY 1997 – REVISED DECEMBER 1998

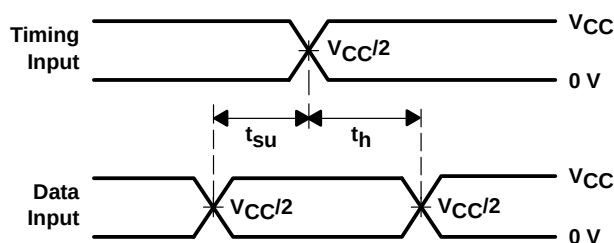
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

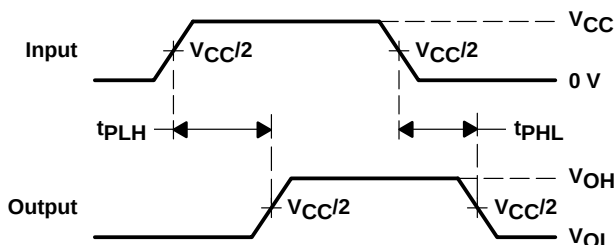


LOAD CIRCUIT

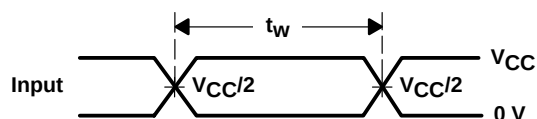
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



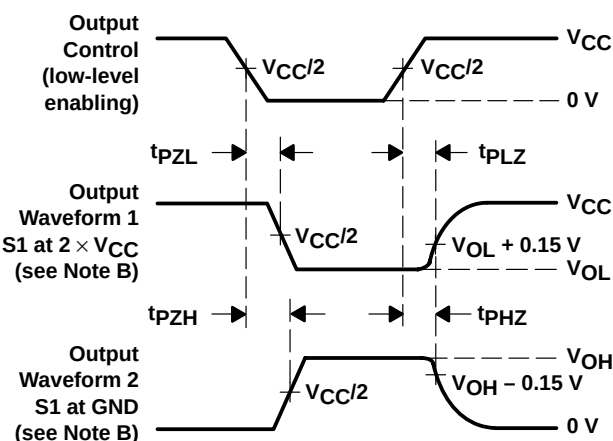
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION

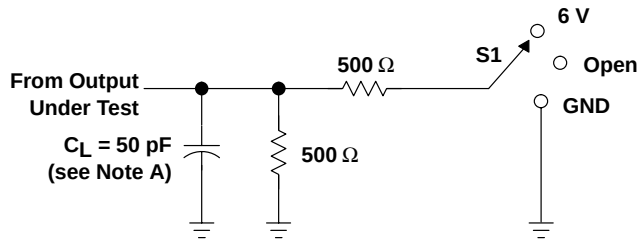


VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

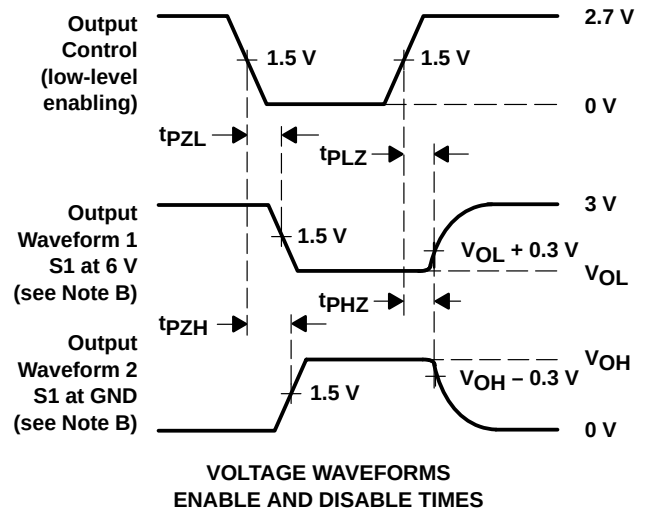
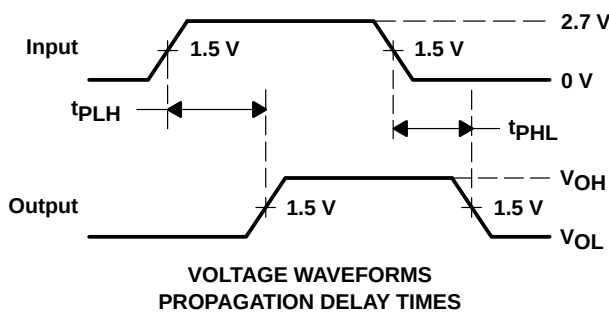
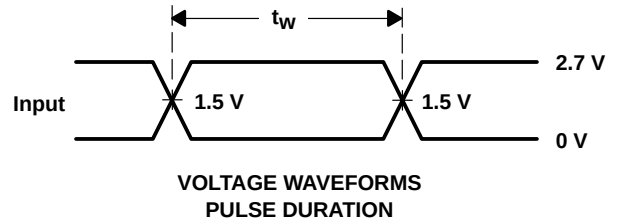
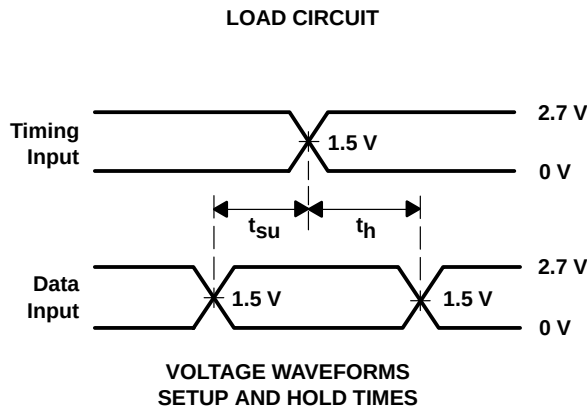
Figure 2. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 2.7\text{ V}$ AND $3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

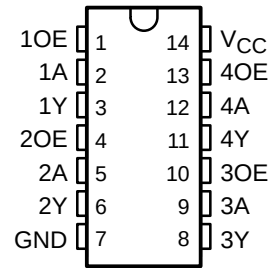
Figure 3. Load Circuit and Voltage Waveforms

SN74ALVC126 QUADRUPLE BUS BUFFER GATE WITH 3-STATE OUTPUTS

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- **EPIC™ (Enhanced-Performance Implanted CMOS) Submicron Process**
- **ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)**
- **Latch-Up Performance Exceeds 250 mA Per JESD 17**
- **Package Options Include Plastic Small-Outline (D), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages**

D, DGV, OR PW PACKAGE
(TOP VIEW)



description

This quadruple bus buffer gate is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVC126 features independent line drivers with 3-state outputs. Each output is disabled when the associated output-enable (OE) input is low.

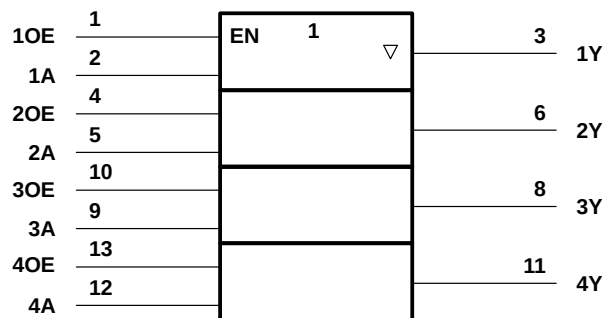
To ensure the high-impedance state during power up or power down, OE should be tied to GND through a pulldown resistor; the minimum value of the resistor is determined by the current-sourcing capability of the driver.

The SN74ALVC126 is characterized for operation from -40°C to 85°C .

FUNCTION TABLE
(each buffer)

INPUTS		OUTPUT Y
OE	A	
H	H	H
H	L	L
L	X	Z

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



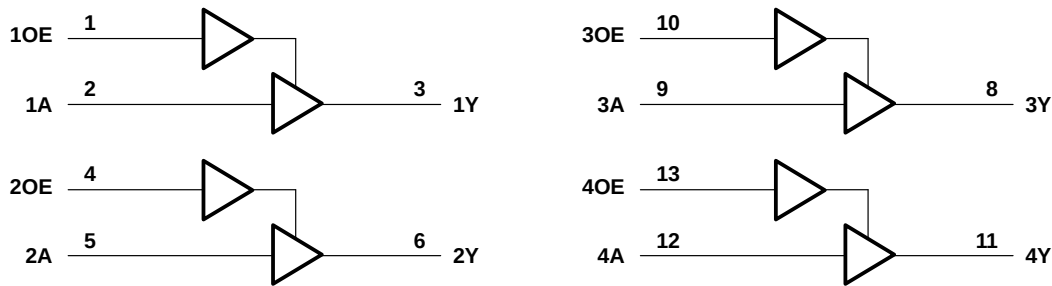
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SN74ALVC126
QUADRUPLE BUS BUFFER GATE
WITH 3-STATE OUTPUTS

SCES111E – JULY 1997 – REVISED FEBRUARY 1999

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3):	
D package	127°C/W
DGV package	182°C/W
PW package	170°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

SN74ALVC126
QUADRUPLE BUS BUFFER GATE
WITH 3-STATE OUTPUTS

SCES111E – JULY 1997 – REVISED FEBRUARY 1999

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate		5		ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

SN74ALVC126

QUADRUPLE BUS BUFFER GATE

WITH 3-STATE OUTPUTS

SCES111E – JULY 1997 – REVISED FEBRUARY 1999

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
		I _{OL} = 12 mA	2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	10			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3.5			pF
	Data inputs			3.5			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	5.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

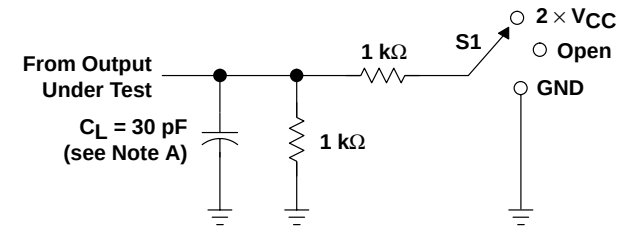
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V ± 0.15 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	Y	1.3	5.6	1	3.4	3.4		1.1	3.1	ns
t _{en}	OE	Y	1	5.9	1	3.8	3.8		1	3.3	ns
t _{dis}	OE	Y	1.8	5.6	1	3.3	4.4		1	3.7	ns

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance per gate	Outputs enabled	C _L = 0, f = 10 MHz	15	17	19	pF
		Outputs disabled		2	2	3	

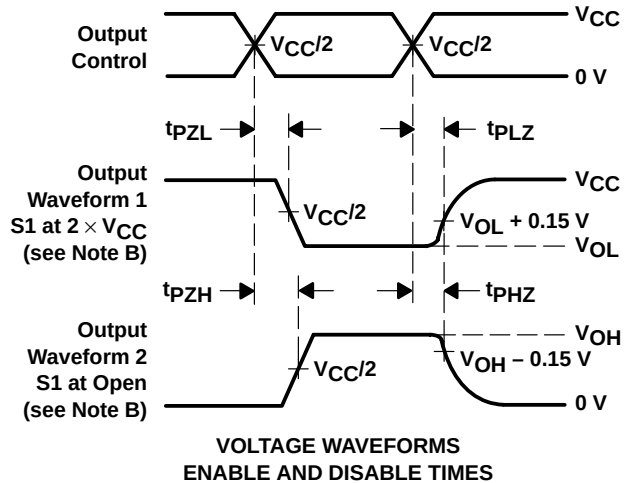
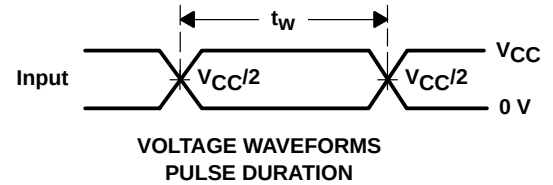
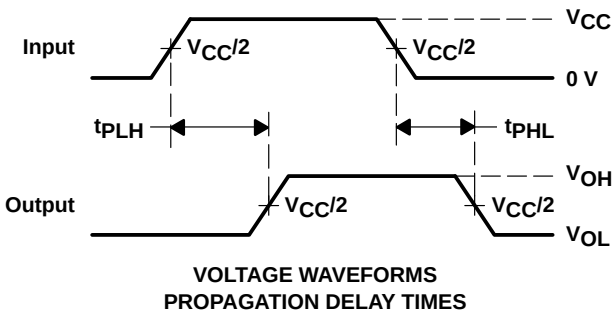
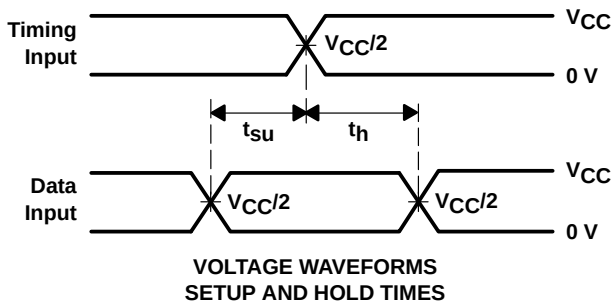


PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8\text{ V} \pm 0.15\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES: A. C_L includes probe and jig capacitance.
 B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 D. The outputs are measured one at a time with one transition per measurement.
 E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 F. t_{PZL} and t_{PZH} are the same as t_{en} .
 G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVC126

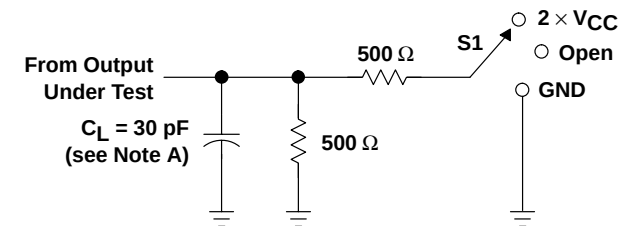
QUADRUPLE BUS BUFFER GATE

WITH 3-STATE OUTPUTS

SCES111E – JULY 1997 – REVISED FEBRUARY 1999

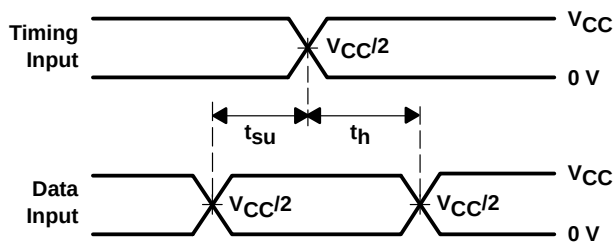
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

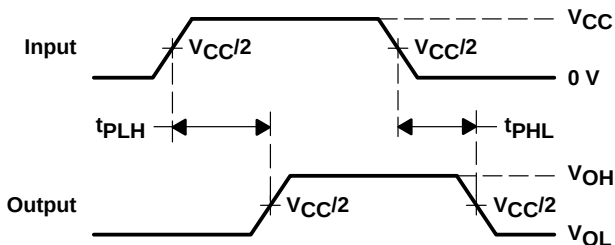


LOAD CIRCUIT

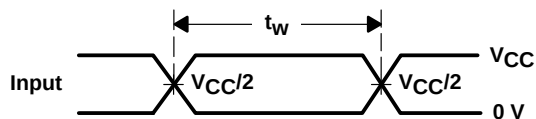
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



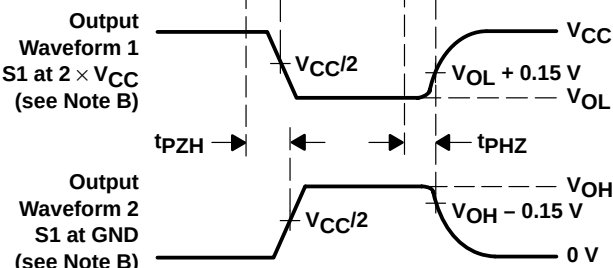
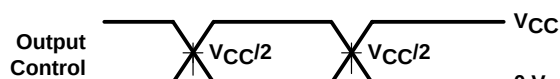
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION

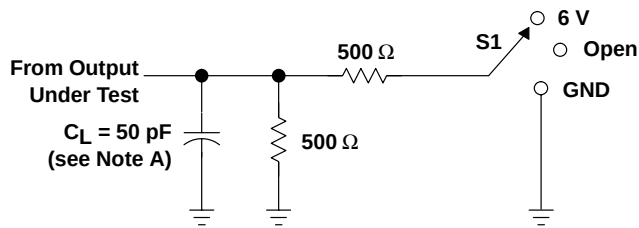


VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

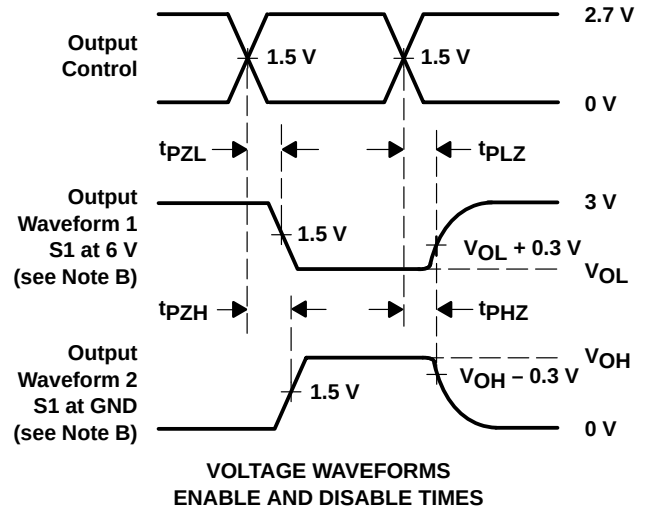
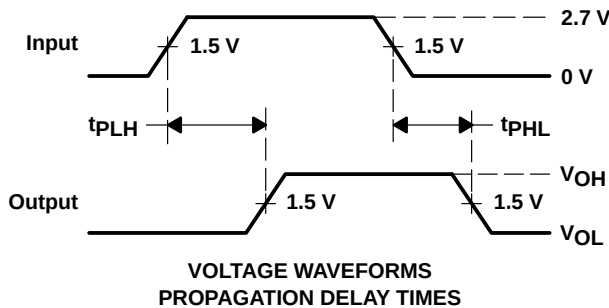
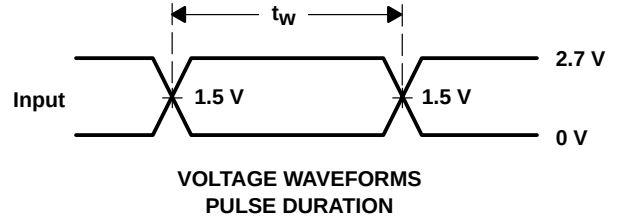
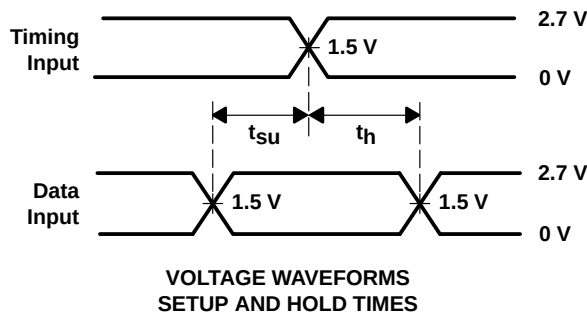
Figure 2. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 2.7\text{ V}$ AND $3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

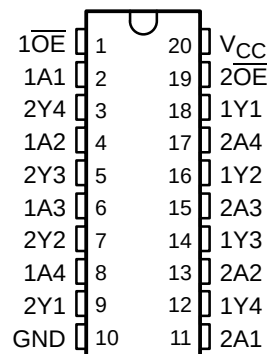
SN74ALVC244

OCTAL BUFFER/DRIVER WITH 3-STATE OUTPUTS

SCES188 – FEBRUARY 1999

- **EPIC™** (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Package Options Include Plastic Small-Outline (DW, NS), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages

DGV, DW, NS, OR PW PACKAGE
(TOP VIEW)



description

This octal buffer/line driver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVC244 is organized as two 4-bit line drivers with separate output-enable ($\overline{OE}$) inputs. When $\overline{OE}$ is low, the device passes data from the A inputs to the Y outputs. When $\overline{OE}$ is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74ALVC244 is characterized for operation from -40°C to 85°C .

FUNCTION TABLE
(each buffer)

INPUTS		OUTPUT
$\overline{OE}$	A	Y
L	H	H
L	L	L
H	X	Z

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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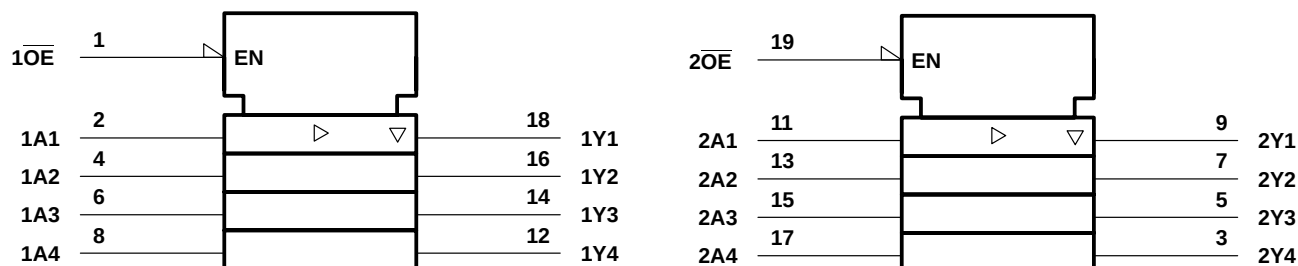
SN74ALVC244

OCTAL BUFFER/DRIVER

WITH 3-STATE OUTPUTS

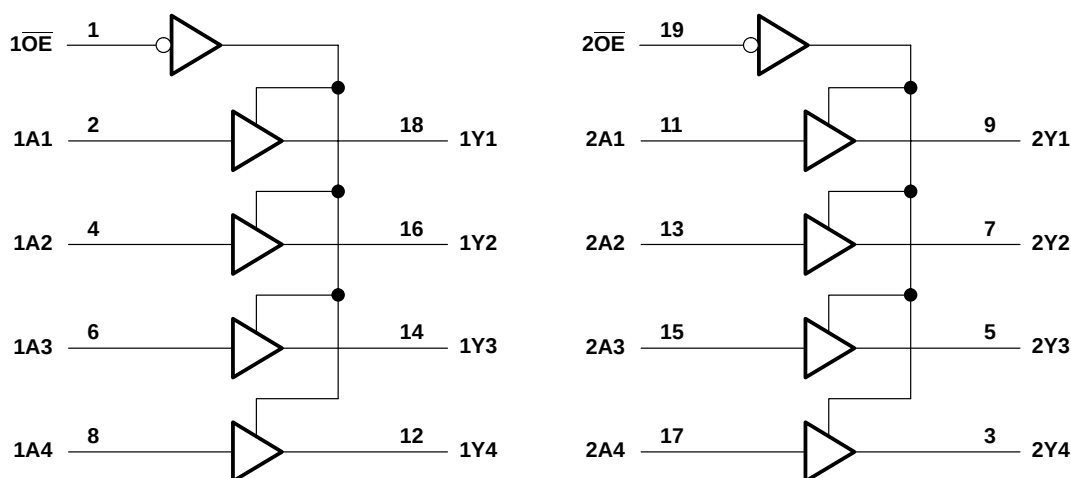
SCES188 – FEBRUARY 1999

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGV package	146°C/W
DW package	97°C/W
NS package	100°C/W
PW package	128°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate		5		ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

SN74ALVC244

OCTAL BUFFER/DRIVER

WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
		I _{OL} = 12 mA	2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	10			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	4.5			pF
	Data inputs			4.5			
C _o	Outputs	V _O = V _{CC} or GND	3.3 V	7.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

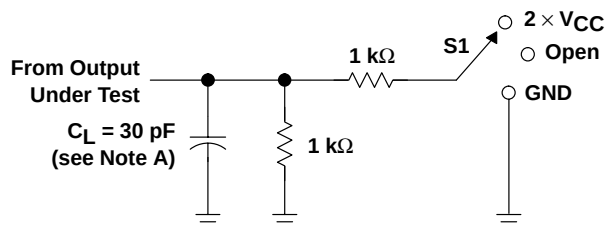
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V ± 0.15 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	Y	1	4.4	1	3.1	3.1		1.1	2.8	ns
t _{en}	$\overline{OE}$	Y	1.8	6.9	1.5	5.4	5.3		1.5	4.5	ns
t _{dis}	$\overline{OE}$	Y	1.8	5.9	1	4.1	4.4		1.7	4.2	ns

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance per buffer/driver	Outputs enabled	C _L = 0, f = 10 MHz	22	23	26	pF
		Outputs disabled		1	1	1	

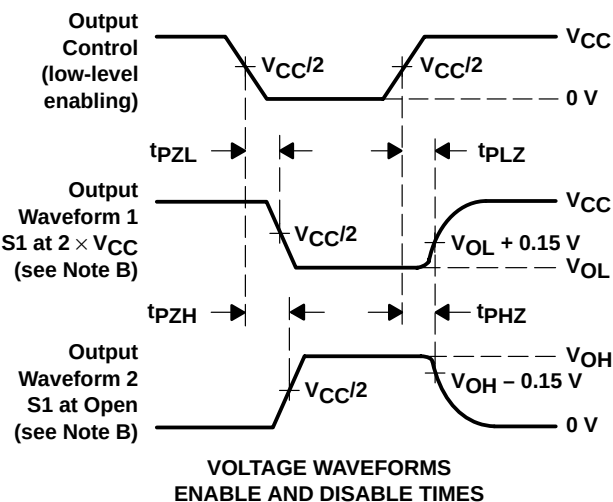
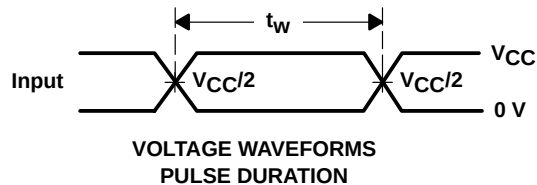
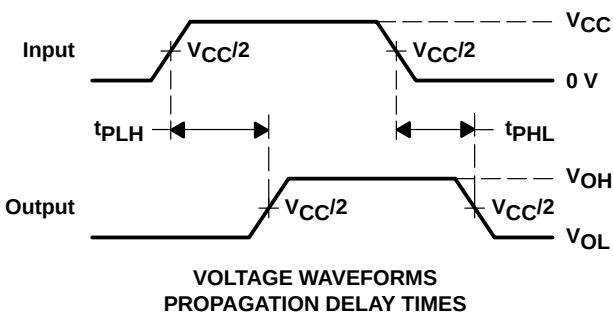
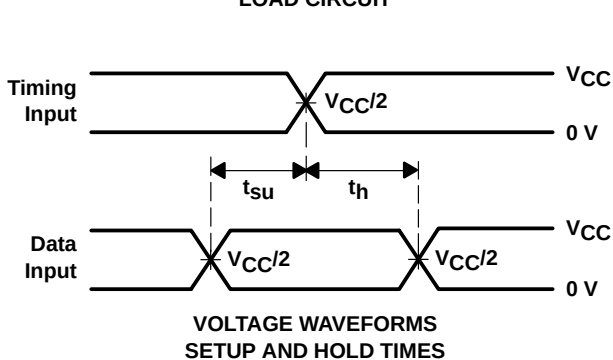


PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVC244

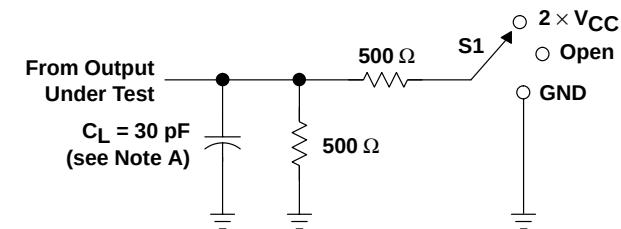
OCTAL BUFFER/DRIVER

WITH 3-STATE OUTPUTS

SCES188 – FEBRUARY 1999

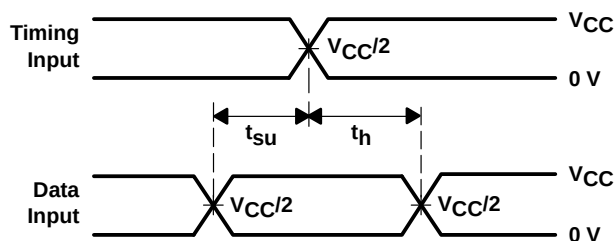
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

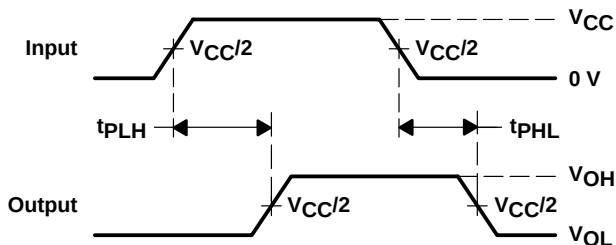


LOAD CIRCUIT

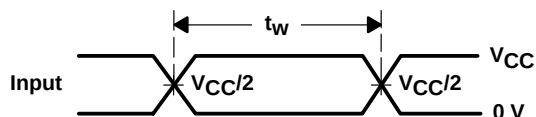
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	$2 \times V_{CC}$
t_{PHZ}/t_{PZH}	GND



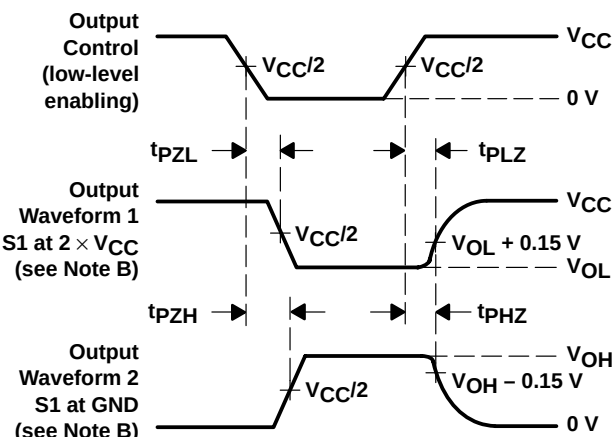
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION

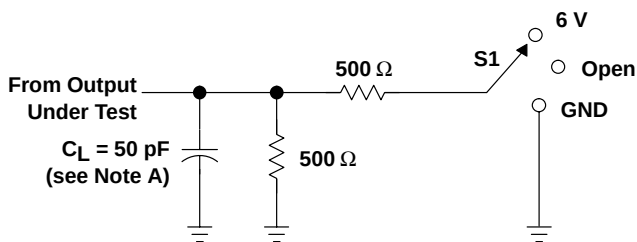


VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

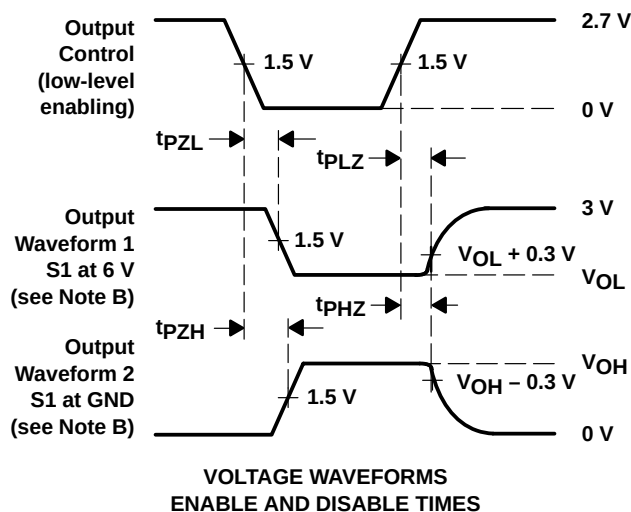
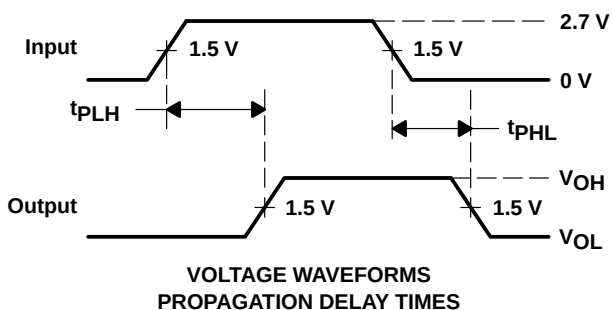
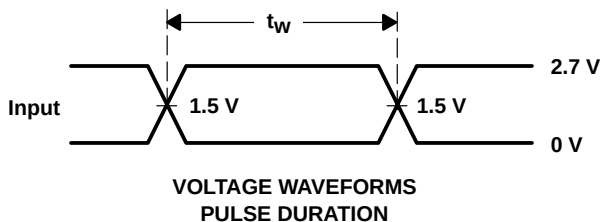
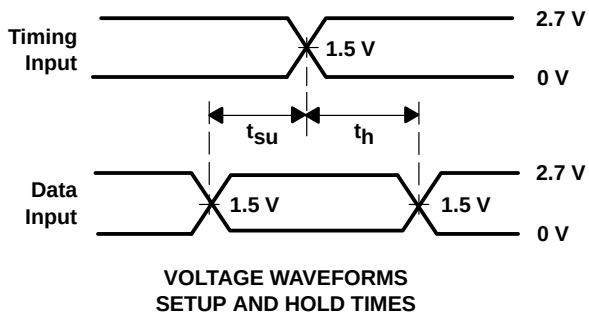
Figure 2. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 2.7\text{ V}$ AND $3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

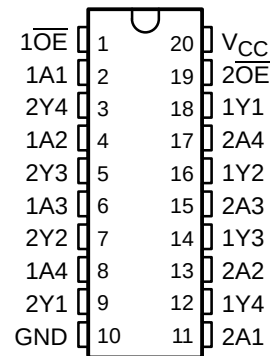
Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH244 OCTAL BUFFER/DRIVER WITH 3-STATE OUTPUTS

SCES112C – JULY 1997 – REVISED FEBRUARY 1999

- **EPIC™** (Enhanced-Performance Implanted CMOS) Submicron Process
- **Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors**
- **ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)**
- **Latch-Up Performance Exceeds 250 mA Per JESD 17**
- **Package Options Include Plastic Small-Outline (DW, NS), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages**

DGV, DW, NS, OR PW PACKAGE
(TOP VIEW)



description

This octal buffer/line driver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH244 is organized as two 4-bit line drivers with separate output-enable ($\overline{OE}$) inputs. When $\overline{OE}$ is low, the device passes data from the A inputs to the Y outputs. When $\overline{OE}$ is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH244 is characterized for operation from -40°C to 85°C .

FUNCTION TABLE
(each buffer)

INPUTS		OUTPUT
$\overline{OE}$	A	Y
L	H	H
L	L	L
H	X	Z

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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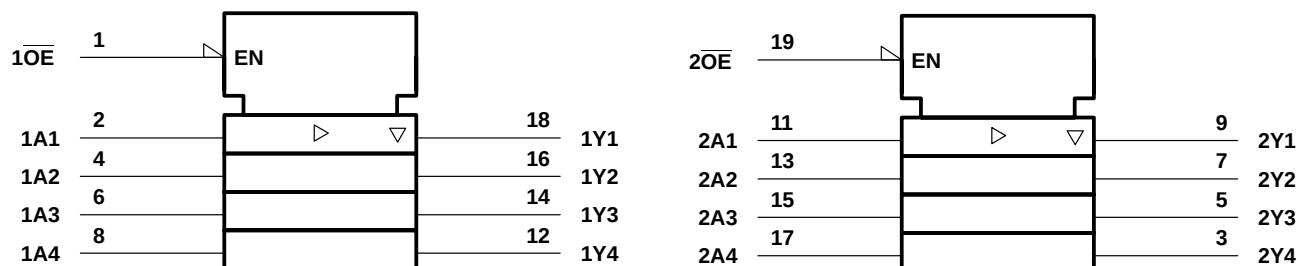
SN74ALVCH244

OCTAL BUFFER/DRIVER

WITH 3-STATE OUTPUTS

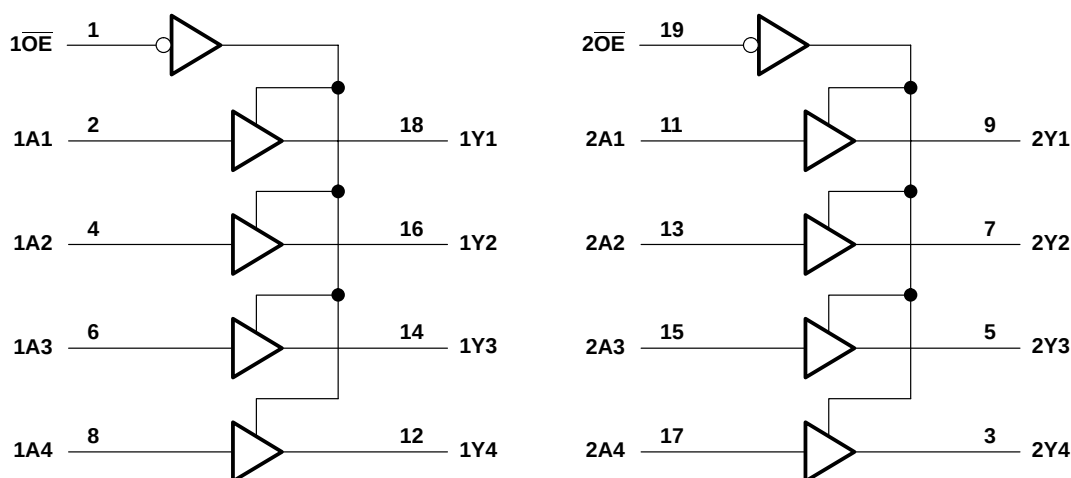
SCES112C – JULY 1997 – REVISED FEBRUARY 1999

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGV package	146°C/W
DW package	97°C/W
NS package	100°C/W
PW package	128°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

SN74ALVCH244
OCTAL BUFFER/DRIVER
WITH 3-STATE OUTPUTS

SCES112C – JULY 1997 – REVISED FEBRUARY 1999

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate		5		ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

SN74ALVCH244

OCTAL BUFFER/DRIVER

WITH 3-STATE OUTPUTS

SCES112C – JULY 1997 – REVISED FEBRUARY 1999

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)	V _I = 0.58 V	1.65 V	§			µA
	V _I = 1.07 V	1.65 V	§			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	10			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	3.3 V	4.5			pF
	Data inputs		6			
C _O	Outputs	3.3 V	8			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

§ This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	Y	§	1	3.1	3.1	1.1	2.8		ns
t _{en}	$\overline{\text{OE}}$	Y	§	1.5	5.4	5.3	1.5	4.5		ns
t _{dis}	$\overline{\text{OE}}$	Y	§	1	4.1	4.4	1.7	4.2		ns

§ This information was not available at the time of publication.



SN74ALVCH244
OCTAL BUFFER/DRIVER
WITH 3-STATE OUTPUTS

SCES112C – JULY 1997 – REVISED FEBRUARY 1999

operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER			TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$ $\pm 0.2\text{ V}$	$V_{CC} = 3.3\text{ V}$ $\pm 0.3\text{ V}$	UNIT
				TYP	TYP	TYP	
C_{pd} Power dissipation capacitance per buffer/driver	Outputs enabled	$C_L = 0, f = 10\text{ MHz}$		†	22	28	pF
	Outputs disabled			†	1.5	4	

† This information was not available at the time of publication.



SN74ALVCH244

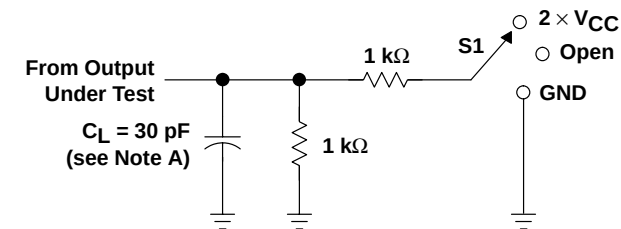
OCTAL BUFFER/DRIVER

WITH 3-STATE OUTPUTS

SCES112C – JULY 1997 – REVISED FEBRUARY 1999

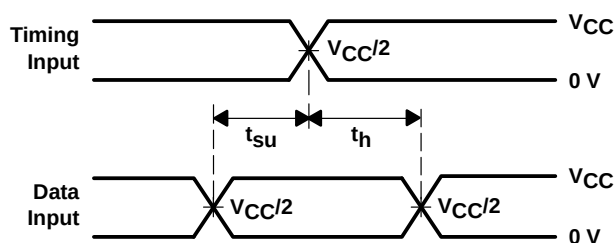
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 1.8 \text{ V}$$

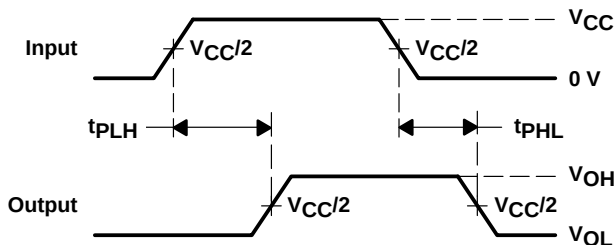


LOAD CIRCUIT

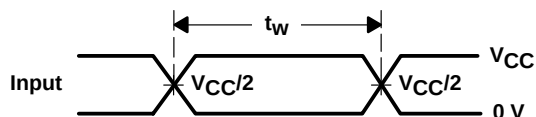
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times$ V_{CC}
t_{PHZ}/t_{PZH}	GND



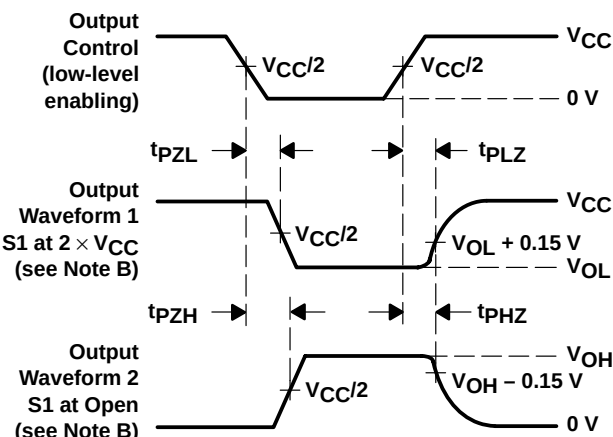
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



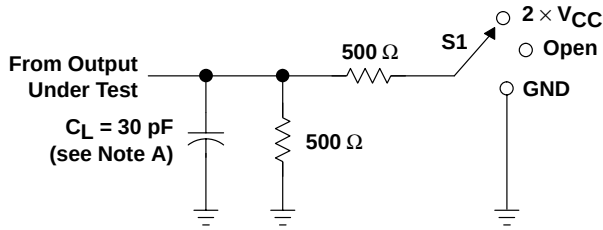
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

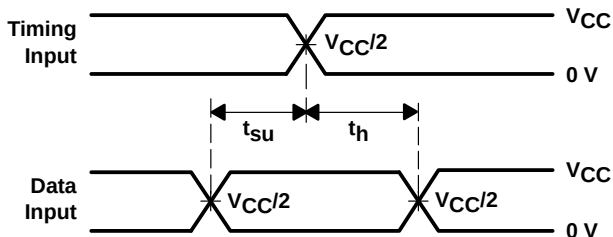
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

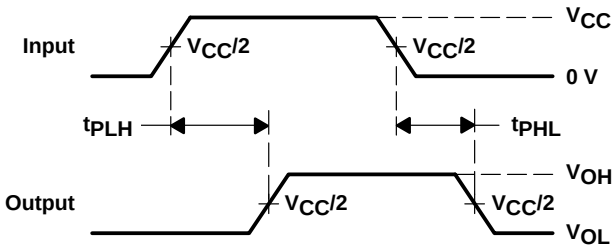


LOAD CIRCUIT

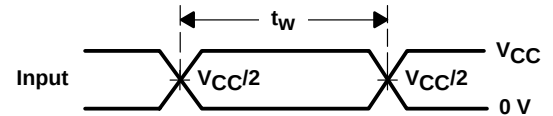
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



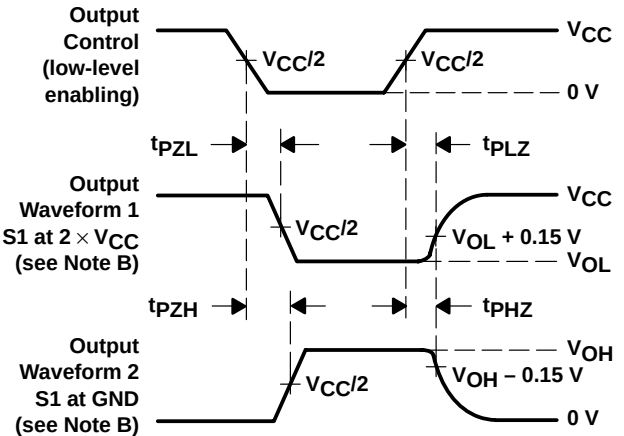
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH244

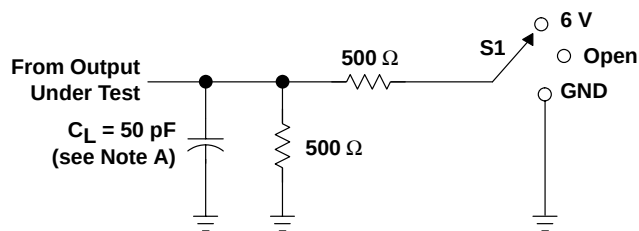
OCTAL BUFFER/DRIVER

WITH 3-STATE OUTPUTS

SCES112C – JULY 1997 – REVISED FEBRUARY 1999

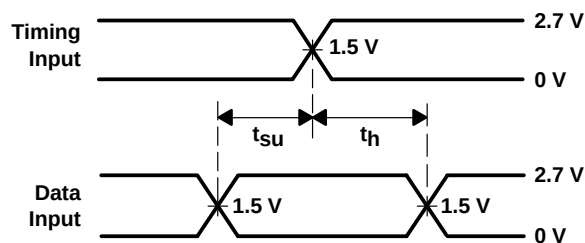
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$

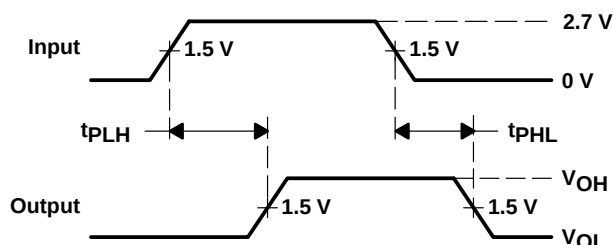


LOAD CIRCUIT

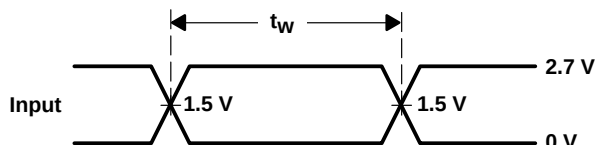
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



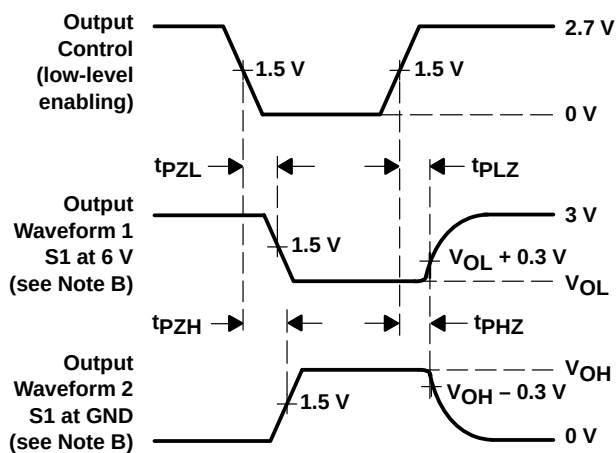
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVC245 OCTAL BUS TRANSCEIVER WITH 3-STATE OUTPUTS

SCES271A – APRIL 1999 – REVISED MAY 1999

- **EPIC™** (Enhanced-Performance Implanted CMOS) Submicron Process
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Package Options Include Plastic Small-Outline (DW), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages

description

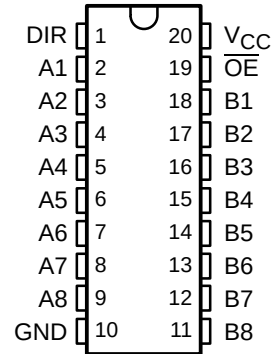
This octal bus transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVC245 is designed for asynchronous communication between data buses. The device transmits data from the A bus to the B bus or from the B bus to the A bus, depending on the logic level at the direction-control (DIR) input. The output-enable ($\overline{OE}$) input can be used to disable the device so the buses are effectively isolated.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74ALVC245 is characterized for operation from -40°C to 85°C .

DGV, DW, OR PW PACKAGE
(TOP VIEW)



FUNCTION TABLE

INPUTS		OPERATION
$\overline{OE}$	DIR	
L	L	B data to A bus
L	H	A data to B bus
H	X	Isolation

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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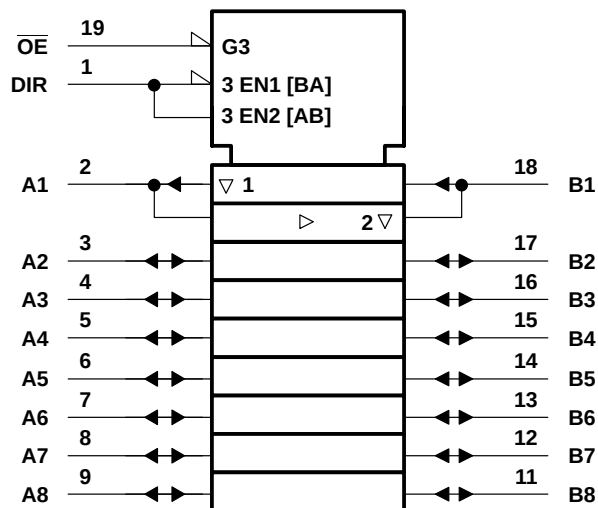
SN74ALVC245

OCTAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

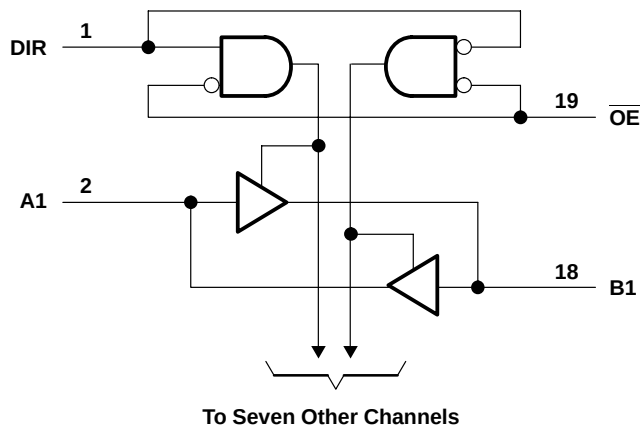
SCES271A – APRIL 1999 – REVISED MAY 1999

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGV package	146°C/W
DW package	97°C/W
PW package	128°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

SN74ALVC245

OCTAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

SCES271A – APRIL 1999 – REVISED MAY 1999

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _{OZ} [‡]	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	10			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs V _I = V _{CC} or GND	3.3 V	4.5			pF
C _{iO}	A or B ports V _O = V _{CC} or GND	3.3 V	11.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] For I/O ports, the parameter I_{OZ} includes the input leakage current.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V ± 0.15 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A or B	B or A	1.5	6	1	3.5	3.6		1.3	3.4	ns
t _{en}	$\overline{\text{OE}}$	A or B	3.4	8.6	2	6	6.3		1.6	5.5	ns
t _{dis}	$\overline{\text{OE}}$	A or B	2.7	8	1	4.8	5.3		1.7	5.5	ns

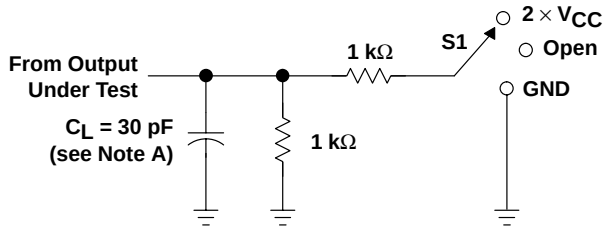
operating characteristics, T_A = 25°C

PARAMETER		TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
			TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance per transceiver	Outputs enabled	25	27	30	pF
		Outputs disabled	0	0	0	



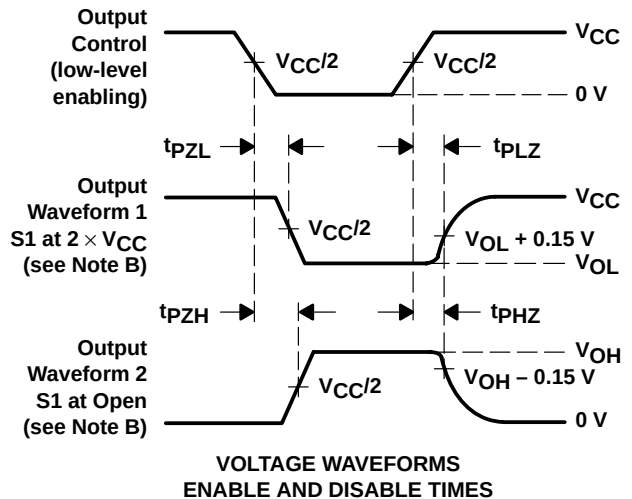
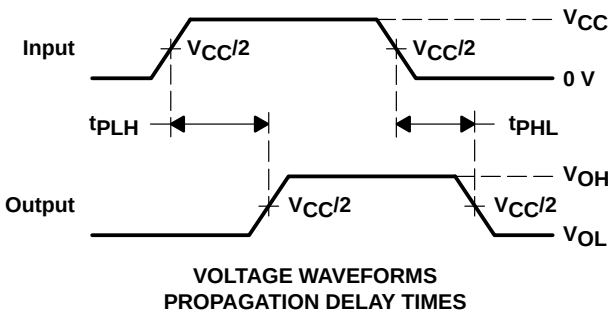
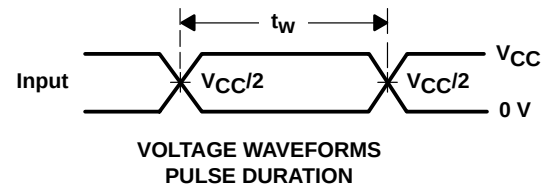
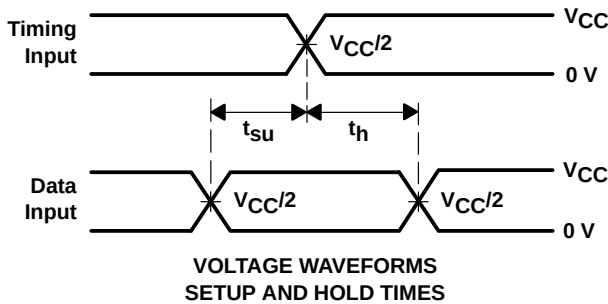
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}$$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVC245

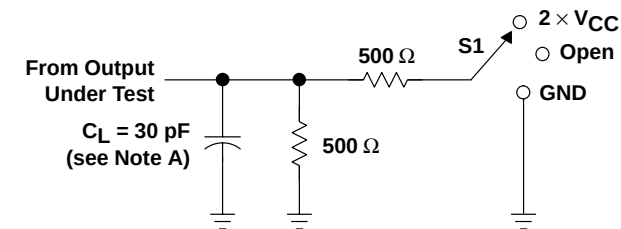
OCTAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

SCES271A – APRIL 1999 – REVISED MAY 1999

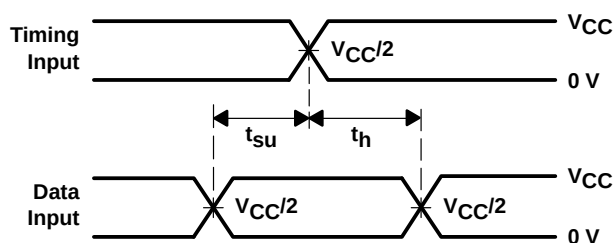
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

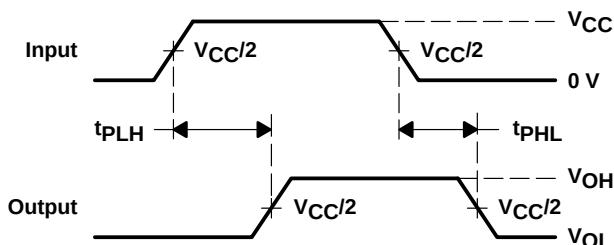


LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



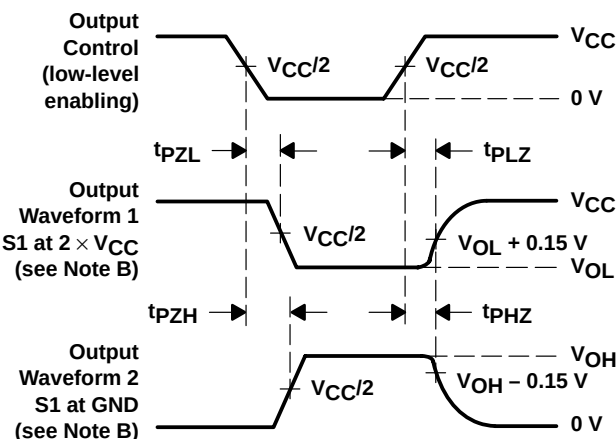
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



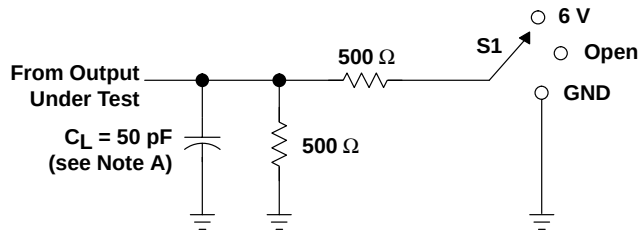
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

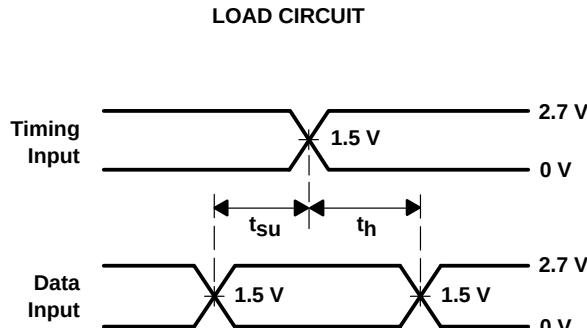
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

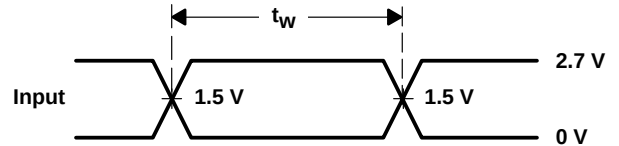


LOAD CIRCUIT

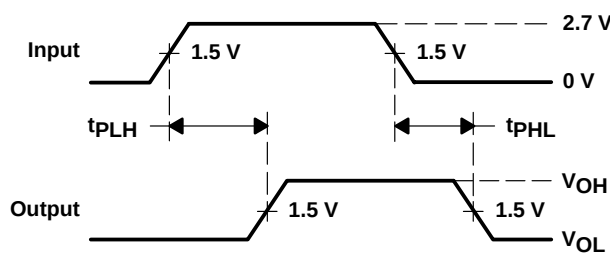
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



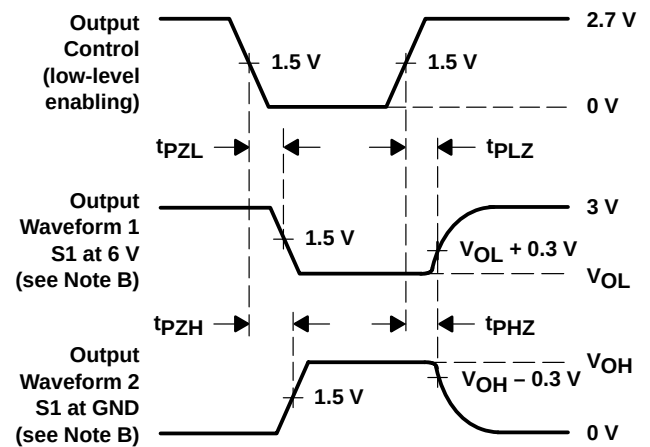
**VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES**



**VOLTAGE WAVEFORMS
PULSE DURATION**



**VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES**



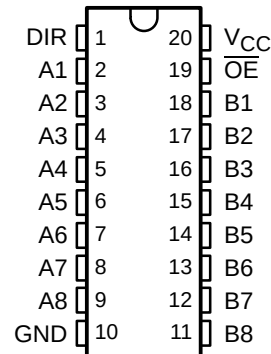
**VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES**

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

- **EPIC™** (Enhanced-Performance Implanted CMOS) Submicron Process
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic Small-Outline (DW), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages

DGV, DW, OR PW PACKAGE
 (TOP VIEW)



description

This octal bus transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH245 is designed for asynchronous communication between data buses. The device transmits data from the A bus to the B bus or from the B bus to the A bus, depending on the logic level at the direction-control (DIR) input. The output-enable ($\overline{OE}$) input can be used to disable the device so the buses are effectively isolated.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH245 is characterized for operation from -40°C to 85°C .

FUNCTION TABLE

INPUTS		OPERATION
$\overline{OE}$	DIR	
L	L	B data to A bus
L	H	A data to B bus
H	X	Isolation

EPIC is a trademark of Texas Instruments Incorporated.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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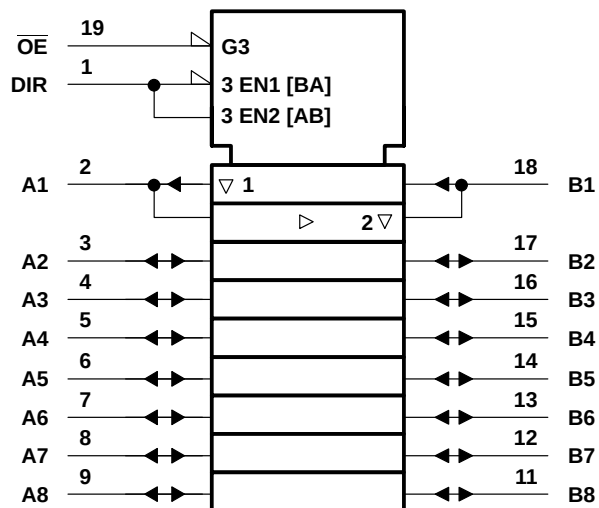
SN74ALVCH245

OCTAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

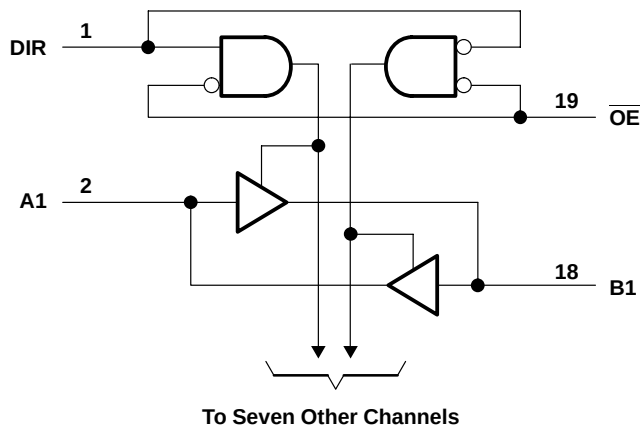
SCES119D – JULY 1997 – REVISED MAY 1999

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGV package	146°C/W
DW package	97°C/W
PW package	128°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

SN74ALVCH245

OCTAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V			0.2	V
	I _{OL} = 4 mA	1.65 V			0.45	
	I _{OL} = 6 mA	2.3 V			0.4	
	I _{OL} = 12 mA	2.3 V			0.7	
		2.7 V			0.4	
	I _{OL} = 24 mA	3 V			0.55	
I _I	V _I = V _{CC} or GND	3.6 V			±5	µA
I _{I(hold)}	V _I = 0.58 V	1.65 V		25		µA
	V _I = 1.07 V	1.65 V		–25		
	V _I = 0.7 V	2.3 V		45		
	V _I = 1.7 V	2.3 V		–45		
	V _I = 0.8 V	3 V		75		
	V _I = 2 V	3 V		–75		
	V _I = 0 to 3.6 V [‡]	3.6 V			±500	
I _{OZ} [§]	V _O = V _{CC} or GND,	3.6 V			±10	µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V			10	µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V			750	µA
C _i	Control inputs	V _I = V _{CC} or GND			4.5	pF
C _{io}	A or B ports	V _O = V _{CC} or GND			12	pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V ± 0.15 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A or B	B or A	1.5	6	1	3.5		3.6	1.3	3.4	ns
t _{en}	$\overline{\text{OE}}$	A or B	3.4	8.6	2	6		6.3	1.6	5.5	ns
t _{dis}	$\overline{\text{OE}}$	A or B	2.7	8	1	4.8		5.3	1.7	5.5	ns

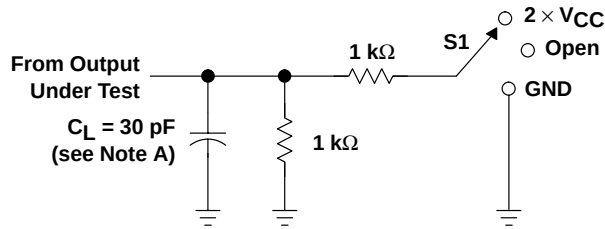
operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance per transceiver	Outputs enabled	C _L = 0, f = 10 MHz	25	28	31	pF
		Outputs disabled		0	0	0	



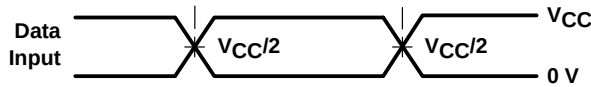
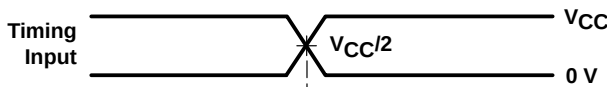
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}$$

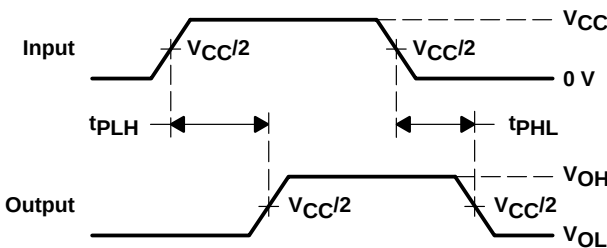


LOAD CIRCUIT

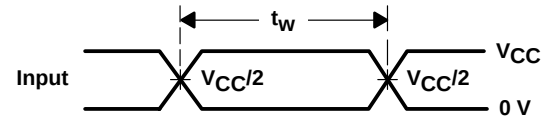
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PHZ}	GND



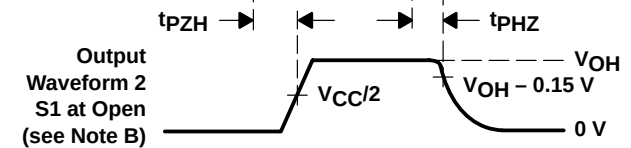
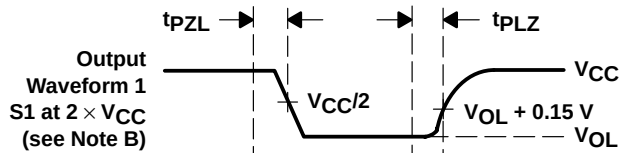
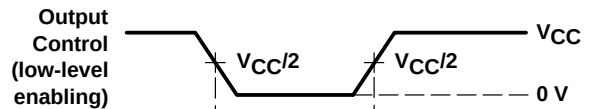
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR $\leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH245

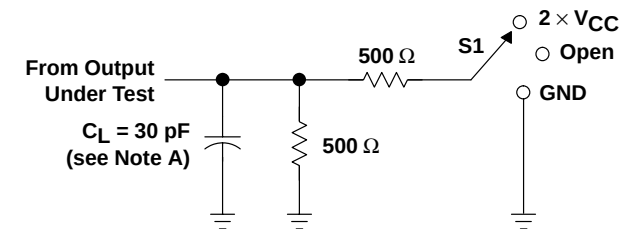
OCTAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

SCES119D – JULY 1997 – REVISED MAY 1999

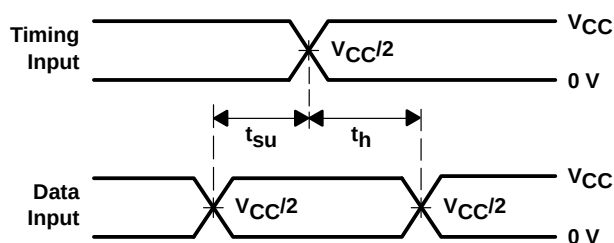
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

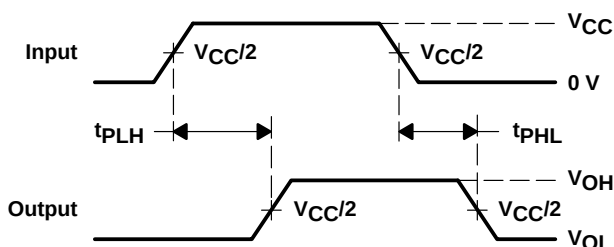


LOAD CIRCUIT

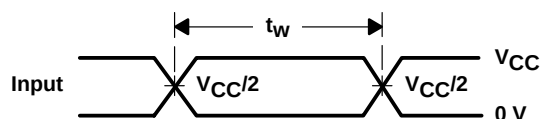
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



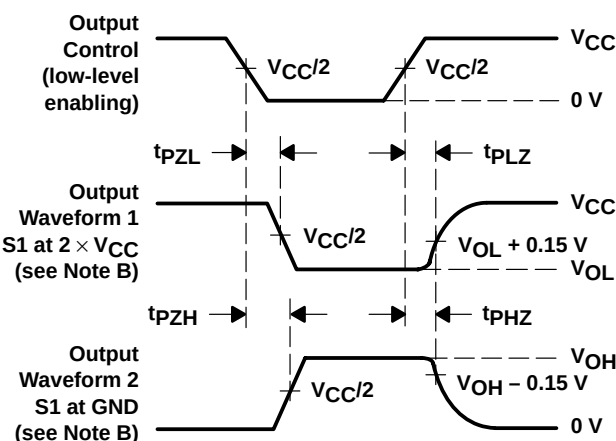
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION

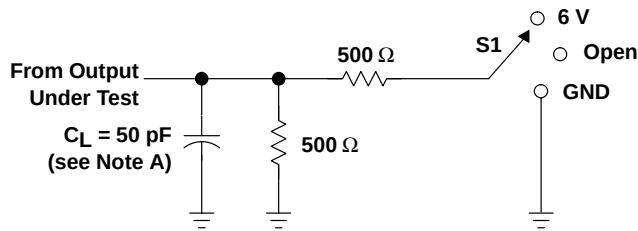


VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
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 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

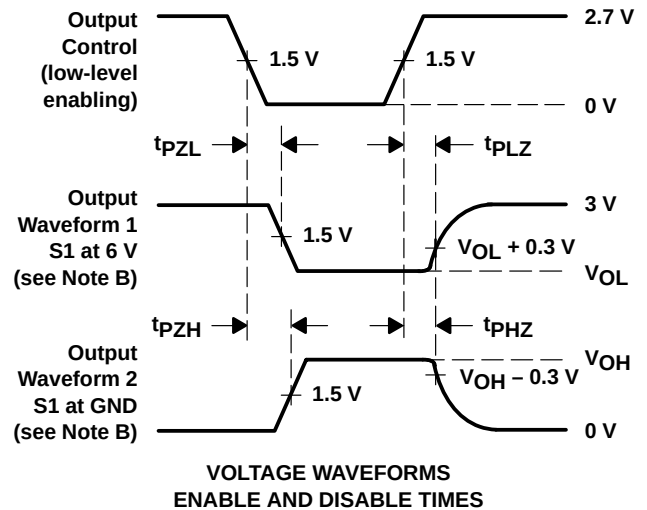
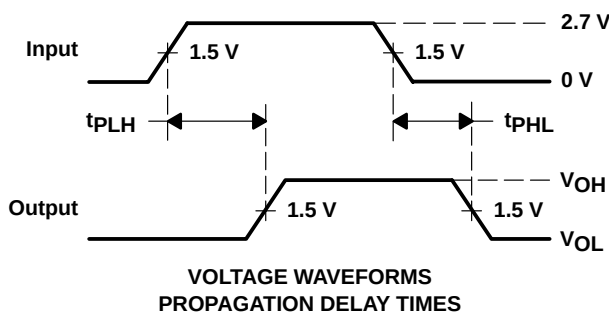
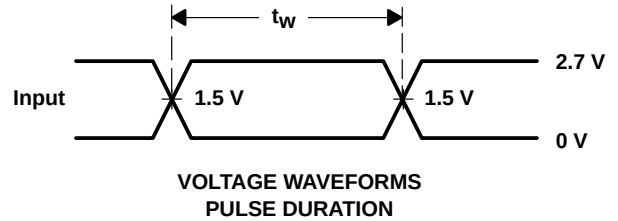
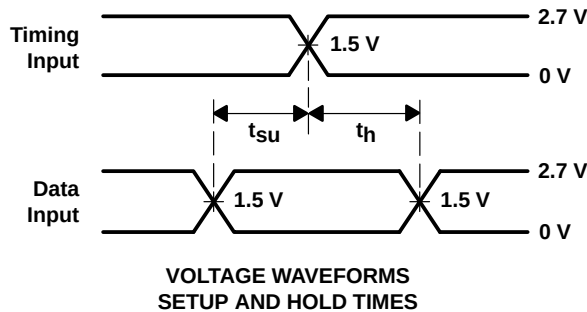
Figure 2. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 2.7\text{ V}$ AND $3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH373 OCTAL TRANSPARENT D-TYPE LATCH WITH 3-STATE OUTPUTS

SCES116D – JULY 1997 – REVISED JANUARY 1999

- **EPIC™** (Enhanced-Performance Implanted CMOS) Submicron Process
- **Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors**
- **Package Options Include Plastic Small-Outline (DW), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages**

description

This octal transparent D-type latch is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH373 is particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers. While the latch-enable (LE) input is high, the Q outputs follow the data (D) inputs. When LE is taken low, the Q outputs are latched at the logic levels set up at the D inputs.

A buffered output-enable ($\overline{OE}$) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

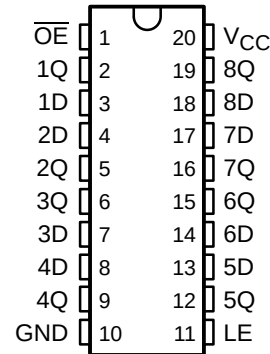
$\overline{OE}$ does not affect the internal operations of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH373 is characterized for operation from -40°C to 85°C .

DGV, DW, OR PW PACKAGE
(TOP VIEW)



FUNCTION TABLE
(each latch)

INPUTS			OUTPUT Q
$\overline{OE}$	LE	D	
L	H	H	H
L	H	L	L
L	L	X	Q_0
H	X	X	Z

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PRODUCT PREVIEW

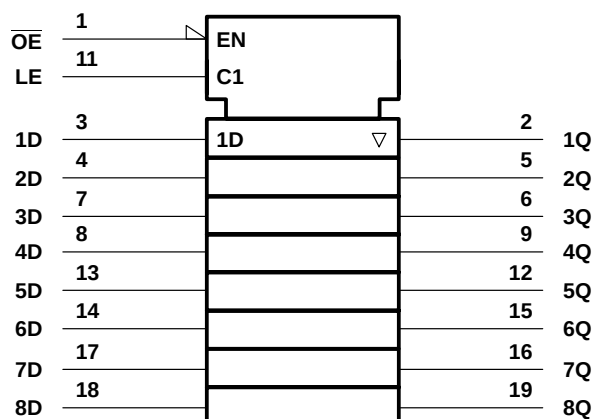
SN74ALVCH373

OCTAL TRANSPARENT D-TYPE LATCH

WITH 3-STATE OUTPUTS

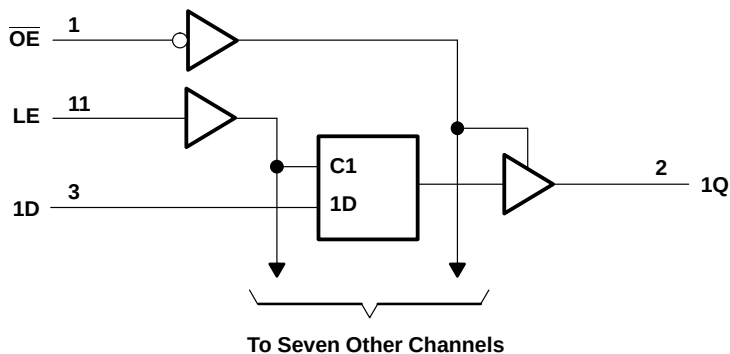
SCES116D – JULY 1997 – REVISED JANUARY 1999

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGV package	146°C/W
DW package	97°C/W
PW package	128°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

SN74ALVCH373
OCTAL TRANSPARENT D-TYPE LATCH
WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate		5		ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

PRODUCT PREVIEW



SN74ALVCH373

OCTAL TRANSPARENT D-TYPE LATCH

WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)	V _I = 0.58 V	1.65 V				µA
	V _I = 1.07 V	1.65 V				
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±425			
I _{OZ}	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	20			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	3.3 V				pF
	Data inputs					
C _O	Outputs	3.3 V				pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t _w	Pulse duration, LE high									ns
t _{su}	Setup time, data before LE↓									ns
t _h	Hold time, data after LE↓									ns

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OCTAL TRANSPARENT D-TYPE LATCH
WITH 3-STATE OUTPUTS

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	D	Q								ns
	LE									
t _{en}	$\overline{\text{OE}}$	Q								ns
t _{dis}	$\overline{\text{OE}}$	Q								ns

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance per latch	Outputs enabled	C _L = 0, f = 10 MHz				pF
		Outputs disabled					

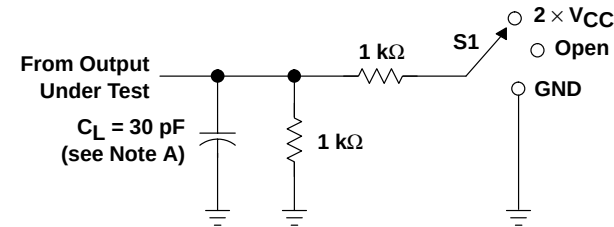
PRODUCT PREVIEW



SN74ALVCH373 OCTAL TRANSPARENT D-TYPE LATCH WITH 3-STATE OUTPUTS

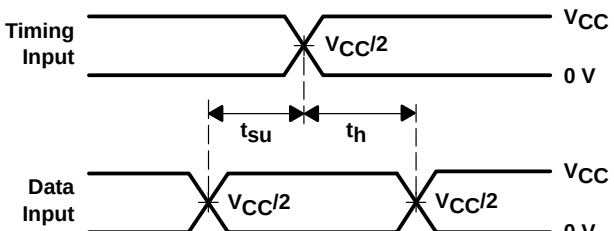
SCES116D – JULY 1997 – REVISED JANUARY 1999

PARAMETER MEASUREMENT INFORMATION $V_{CC} = 1.8\text{ V}$

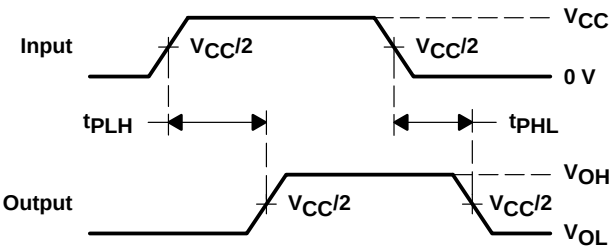


LOAD CIRCUIT

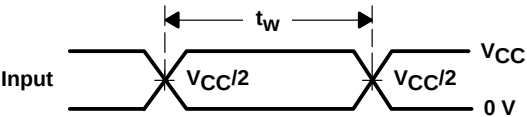
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	$2 \times V_{CC}$
t_{PHZ}/t_{PHZ}	GND



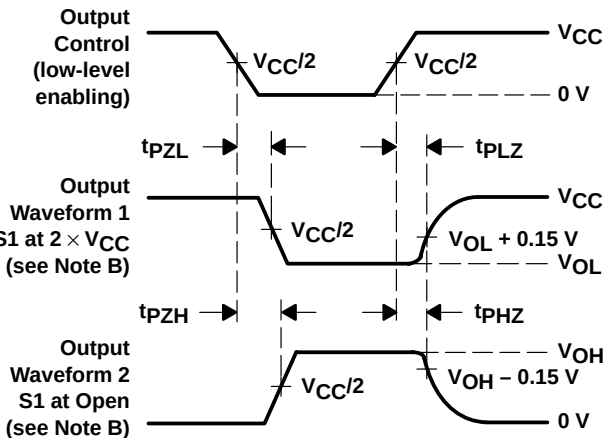
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



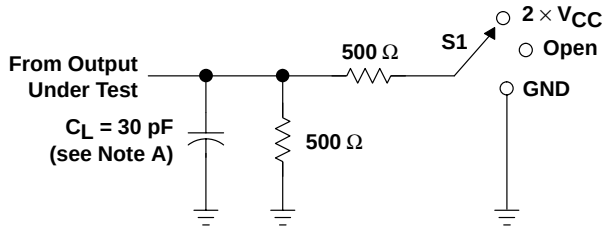
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

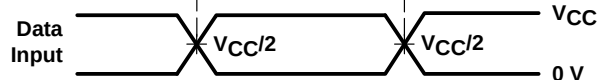
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

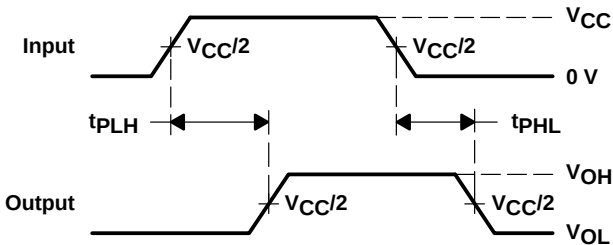


LOAD CIRCUIT

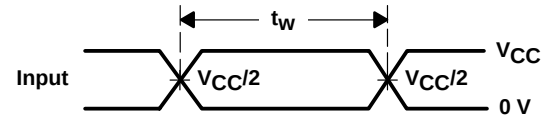
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



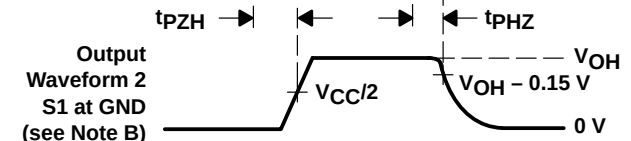
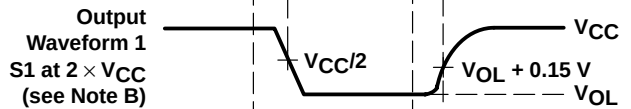
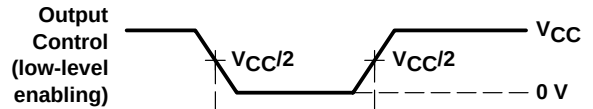
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

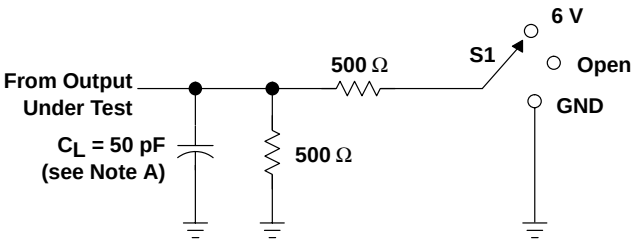
- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR $\leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
D. The outputs are measured one at a time with one transition per measurement.
E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
F. t_{PZL} and t_{PZH} are the same as t_{en} .
G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH373 OCTAL TRANSPARENT D-TYPE LATCH WITH 3-STATE OUTPUTS

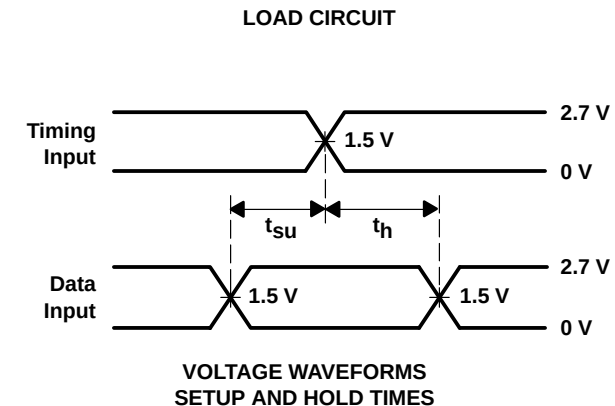
SCES116D – JULY 1997 – REVISED JANUARY 1999

PARAMETER MEASUREMENT INFORMATION $V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

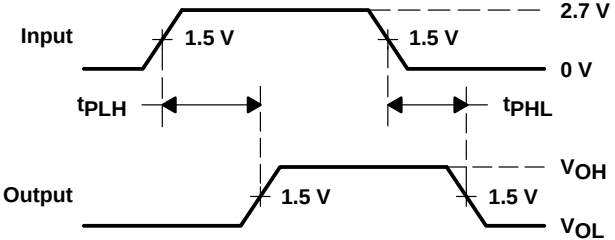


LOAD CIRCUIT

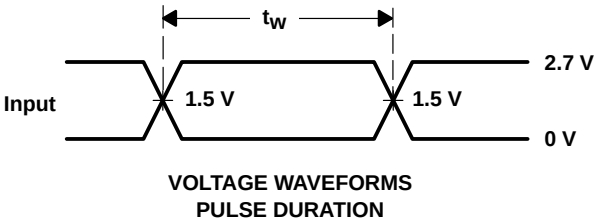
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



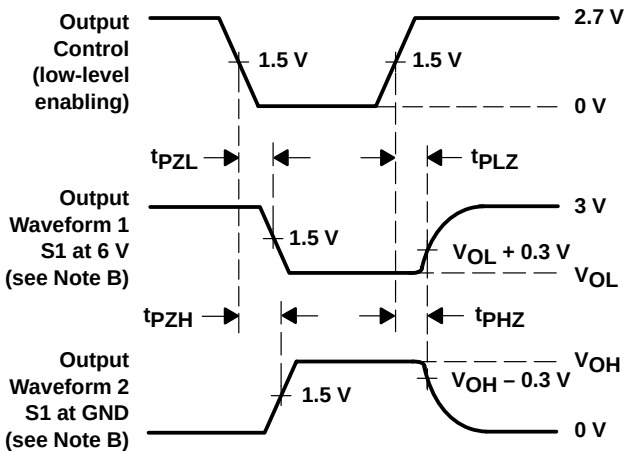
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH374

OCTAL POSITIVE EDGE-TRIGGERED D-TYPE FLIP-FLOP WITH 3-STATE OUTPUTS

SCES118D – JULY 1997 – REVISED JANUARY 1999

- **EPIC™** (Enhanced-Performance Implanted CMOS) Submicron Process
- **Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors**
- **Package Options Include Plastic Small-Outline (DW), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages**

description

This octal edge-triggered D-type flip-flop is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH374 is particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers. On the positive transition of the clock (CLK) input, the Q outputs are set to the logic levels at the data (D) inputs.

A buffered output-enable ($\overline{OE}$) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

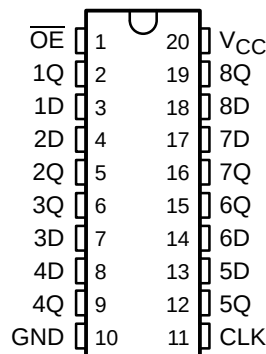
$\overline{OE}$ does not affect internal operations of the latch. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH374 is characterized for operation from -40°C to 85°C .

DGV, DW, OR PW PACKAGE
(TOP VIEW)



FUNCTION TABLE
(each flip-flop)

INPUTS			OUTPUT
$\overline{OE}$	CLK	D	Q
L	$\uparrow$	H	H
L	$\uparrow$	L	L
L	H or L	X	Q_0
H	X	X	Z

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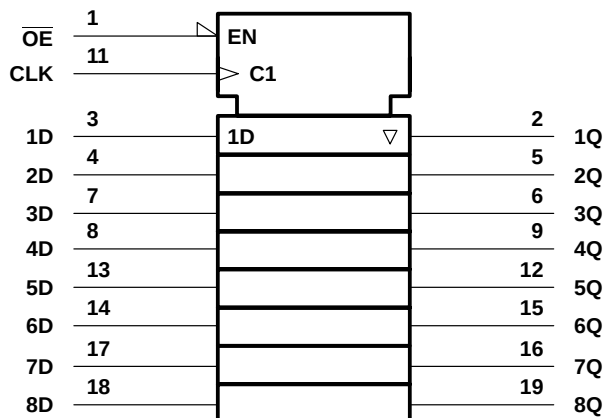
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SN74ALVCH374

OCTAL POSITIVE EDGE-TRIGGERED D-TYPE FLIP-FLOP WITH 3-STATE OUTPUTS

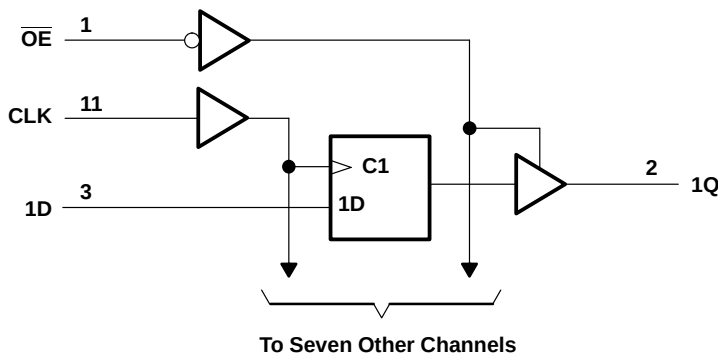
SCES118D – JULY 1997 – REVISED JANUARY 1999

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGV package	146°C/W
DW package	97°C/W
PW package	128°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

SN74ALVCH374
OCTAL POSITIVE EDGE-TRIGGERED D-TYPE FLIP-FLOP
WITH 3-STATE OUTPUTS

SCES118D – JULY 1997 – REVISED JANUARY 1999

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate		5		ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

PRODUCT PREVIEW



SN74ALVCH374

OCTAL POSITIVE EDGE-TRIGGERED D-TYPE FLIP-FLOP WITH 3-STATE OUTPUTS

SCES118D – JULY 1997 – REVISED JANUARY 1999

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 μA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA		2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 μA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA		2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND		3.6 V	±5			μA
I _I (hold)	V _I = 0.58 V		1.65 V				μA
	V _I = 1.07 V		1.65 V				
	V _I = 0.7 V		2.3 V	45			
	V _I = 1.7 V		2.3 V	–45			
	V _I = 0.8 V		3 V	75			
	V _I = 2 V		3 V	–75			
	V _I = 0 to 3.6 V [‡]		3.6 V	±425			
I _{OZ}	V _O = V _{CC} or GND		3.6 V	±10			μA
I _{CC}	V _I = V _{CC} or GND, I _O = 0		3.6 V	20			μA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			μA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V				pF
	Data inputs						
C _O	Outputs	V _O = V _{CC} or GND	3.3 V				pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency									MHz
t _w	Pulse duration, CLK high or low									ns
t _{su}	Setup time, data before CLK↑									ns
t _h	Hold time, data after CLK↑									ns



SN74ALVCH374
OCTAL POSITIVE EDGE-TRIGGERED D-TYPE FLIP-FLOP
WITH 3-STATE OUTPUTS

SCES118D – JULY 1997 – REVISED JANUARY 1999

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}										MHz
t _{pd}	CLK	Q								ns
t _{en}	$\overline{\text{OE}}$	Q								ns
t _{dis}	$\overline{\text{OE}}$	Q								ns

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance per flip-flop	Outputs enabled	C _L = 0, f = 10 MHz				pF
		Outputs disabled					

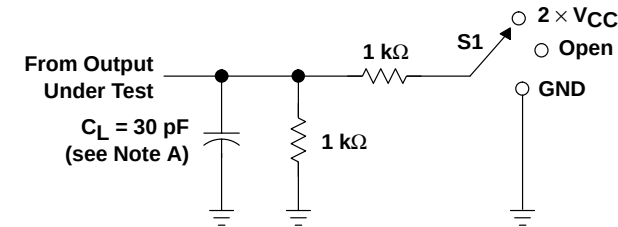
PRODUCT PREVIEW



SN74ALVCH374 OCTAL POSITIVE EDGE-TRIGGERED D-TYPE FLIP-FLOP WITH 3-STATE OUTPUTS

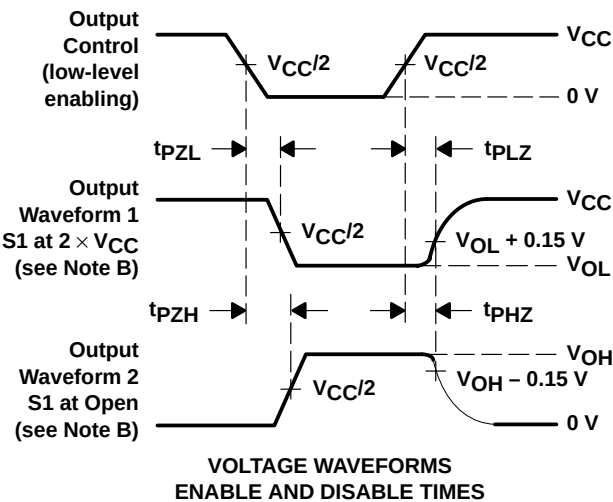
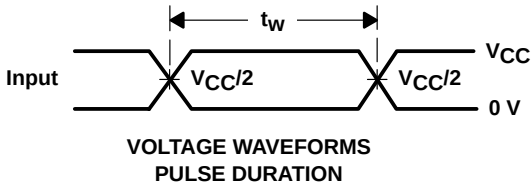
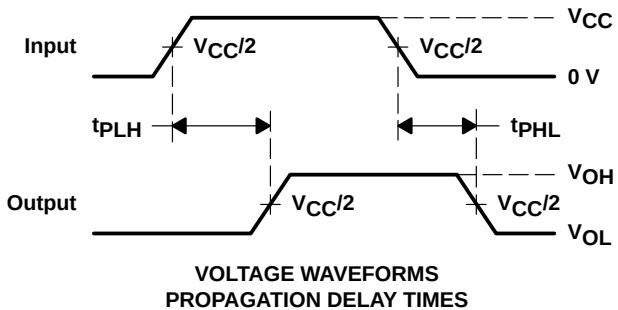
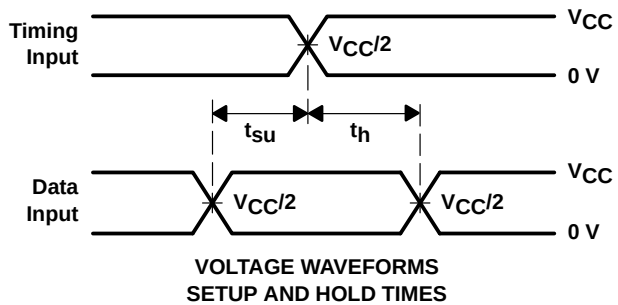
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PARAMETER MEASUREMENT INFORMATION $V_{CC} = 1.8\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PHZ}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

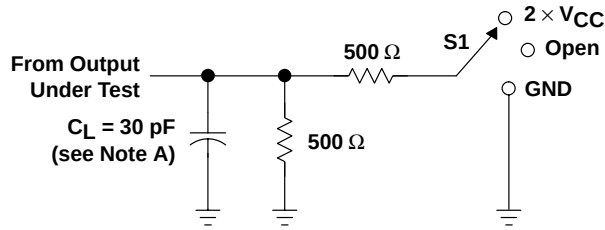
SN74ALVCH374

OCTAL POSITIVE EDGE-TRIGGERED D-TYPE FLIP-FLOP WITH 3-STATE OUTPUTS

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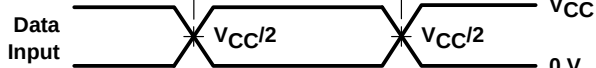
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

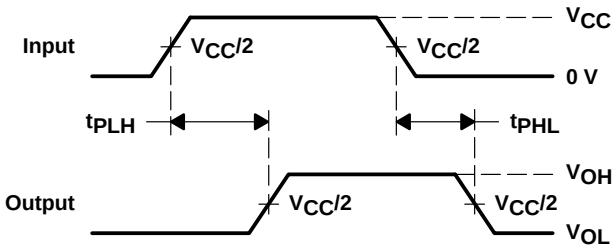


LOAD CIRCUIT

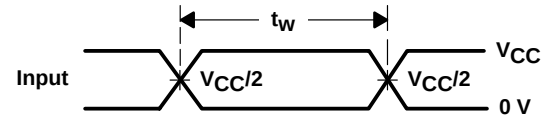
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PHZ}	GND



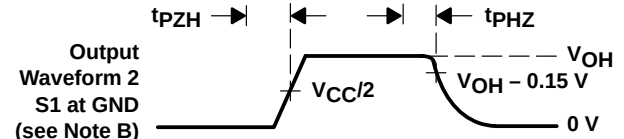
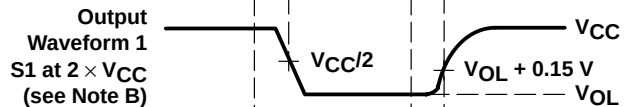
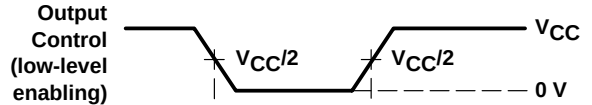
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

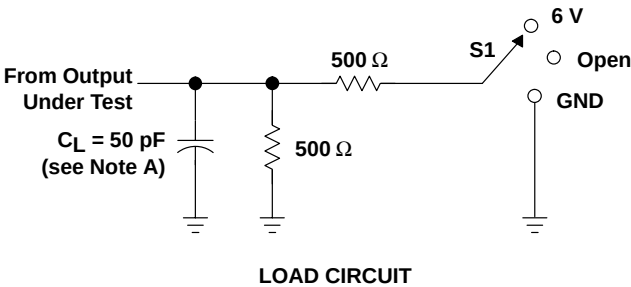
Figure 2. Load Circuit and Voltage Waveforms

PRODUCT PREVIEW

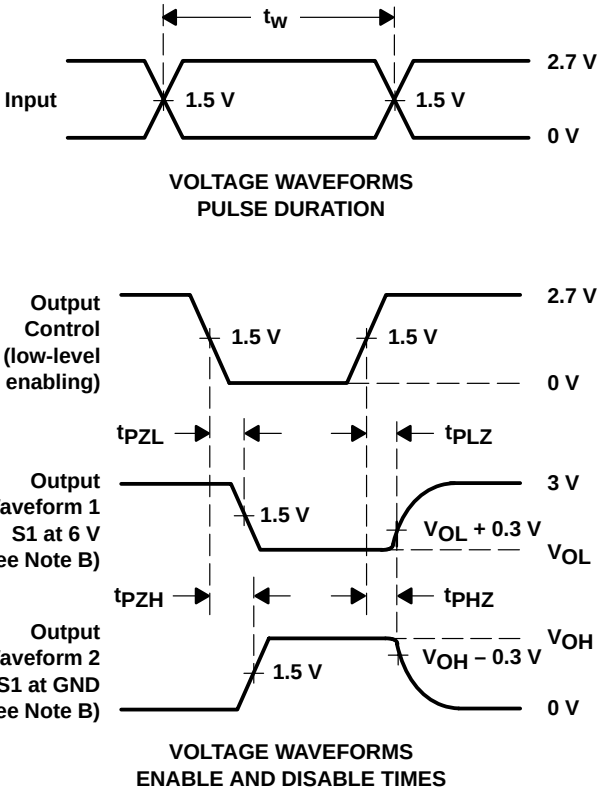
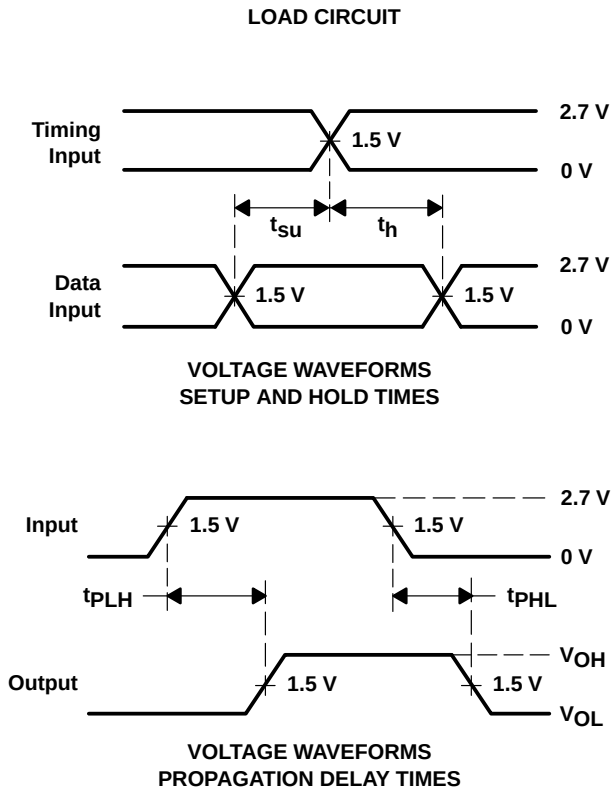
SN74ALVCH374 OCTAL POSITIVE EDGE-TRIGGERED D-TYPE FLIP-FLOP WITH 3-STATE OUTPUTS

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PARAMETER MEASUREMENT INFORMATION $V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

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SN74ALVCH16240

16-BIT BUFFER/DRIVER

WITH 3-STATE OUTPUTS

SCES045C – JULY 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 16-bit buffer/driver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16240 is designed specifically to improve the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters.

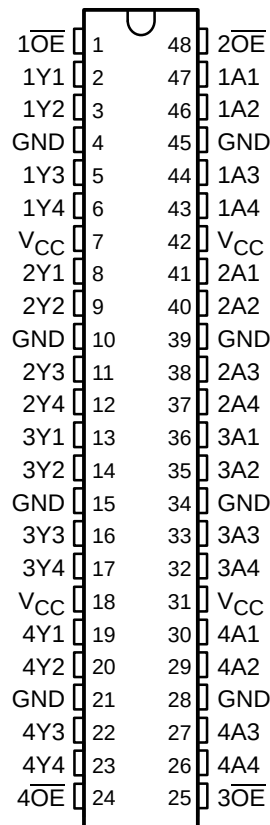
The device can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. It provides inverting outputs and symmetrical active-low output-enable ($\overline{OE}$) inputs.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16240 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)



FUNCTION TABLE
(each 4-bit buffer)

INPUTS		OUTPUT
$\overline{OE}$	A	Y
L	H	L
L	L	H
H	X	Z

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



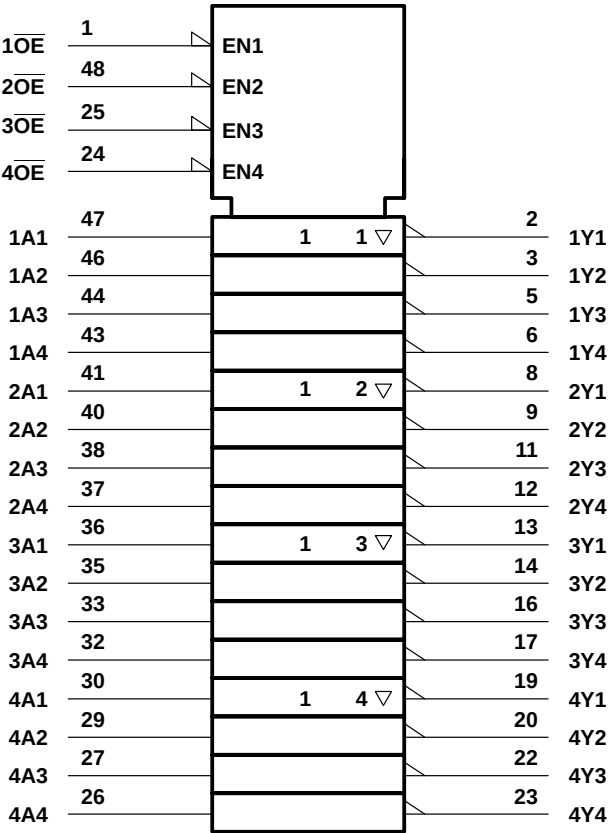
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16-BIT BUFFER/DRIVER
WITH 3-STATE OUTPUTS

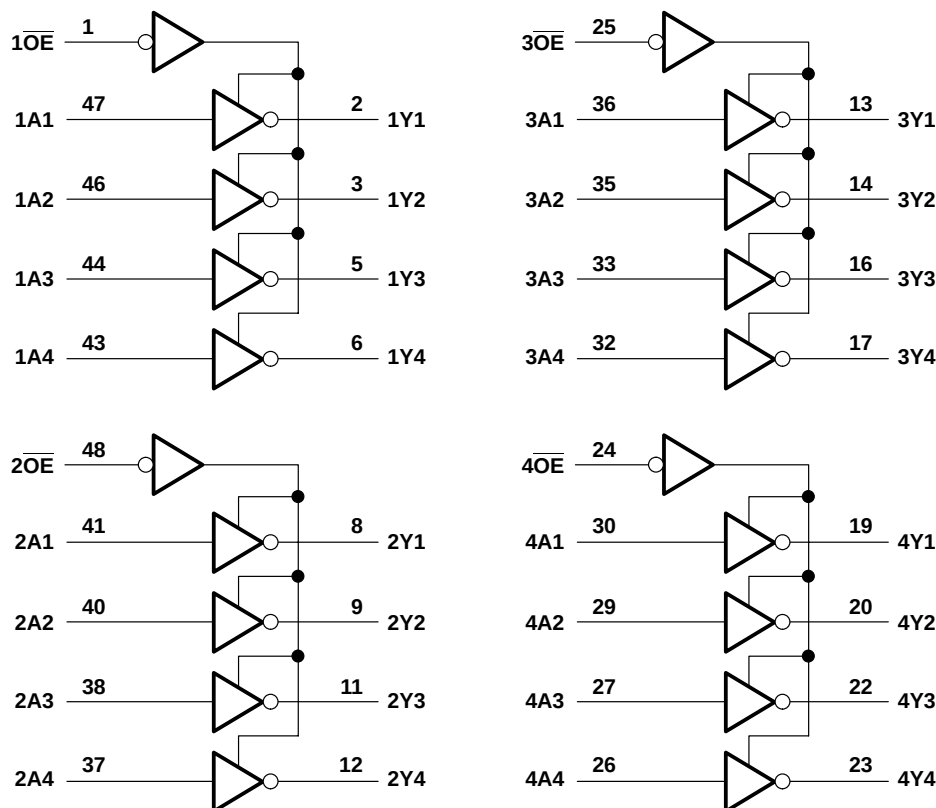
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logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	89°C/W
DL package	94°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

SN74ALVCH16240

16-BIT BUFFER/DRIVER

WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–4	mA
		$V_{CC} = 2.3 \text{ V}$	–12	
		$V_{CC} = 2.7 \text{ V}$	–12	
		$V_{CC} = 3 \text{ V}$	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	4	mA
		$V_{CC} = 2.3 \text{ V}$	12	
		$V_{CC} = 2.7 \text{ V}$	12	
		$V_{CC} = 3 \text{ V}$	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

SN74ALVCH16240
16-BIT BUFFER/DRIVER
WITH 3-STATE OUTPUTS

SCES045C – JULY 1995 – REVISED FEBRUARY 1999

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = −100 μA	1.65 V to 3.6 V	V _{CC} −0.2			V
		I _{OH} = −4 mA	1.65 V	1.2			
		I _{OH} = −6 mA	2.3 V	2			
	I _{OH} = −12 mA		2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
	I _{OH} = −24 mA	3 V	2				
V _{OL}		I _{OL} = 100 μA	1.65 V to 3.6 V			0.2	V
		I _{OL} = 4 mA	1.65 V			0.45	
		I _{OL} = 6 mA	2.3 V			0.4	
	I _{OL} = 12 mA		2.3 V			0.7	
			2.7 V			0.4	
	I _{OL} = 24 mA	3 V			0.55		
I _I	V _I = V _{CC} or GND		3.6 V			±5	μA
I _I (hold)		V _I = 0.58 V	1.65 V	25			μA
		V _I = 1.07 V	1.65 V	−25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	−45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	−75			
		V _I = 0 to 3.6 V [‡]	3.6 V			±500	
I _{OZ}	V _O = V _{CC} or GND		3.6 V			±10	μA
I _{CC}	V _I = V _{CC} or GND, I _O = 0		3.6 V			40	μA
ΔI _{CC}		One input at V _{CC} − 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V			750	μA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3		pF	
	Data inputs			6			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7		pF	

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	Y	§	1	5.3	5.3		1	3.9	ns
t _{en}	$\overline{\text{OE}}$	Y	§	1	6.4	6.1		1	5	ns
t _{dis}	$\overline{\text{OE}}$	Y	§	1	5.4	4.8		1	4.4	ns

§ This information was not available at the time of publication.



SN74ALVCH16240
16-BIT BUFFER/DRIVER
WITH 3-STATE OUTPUTS

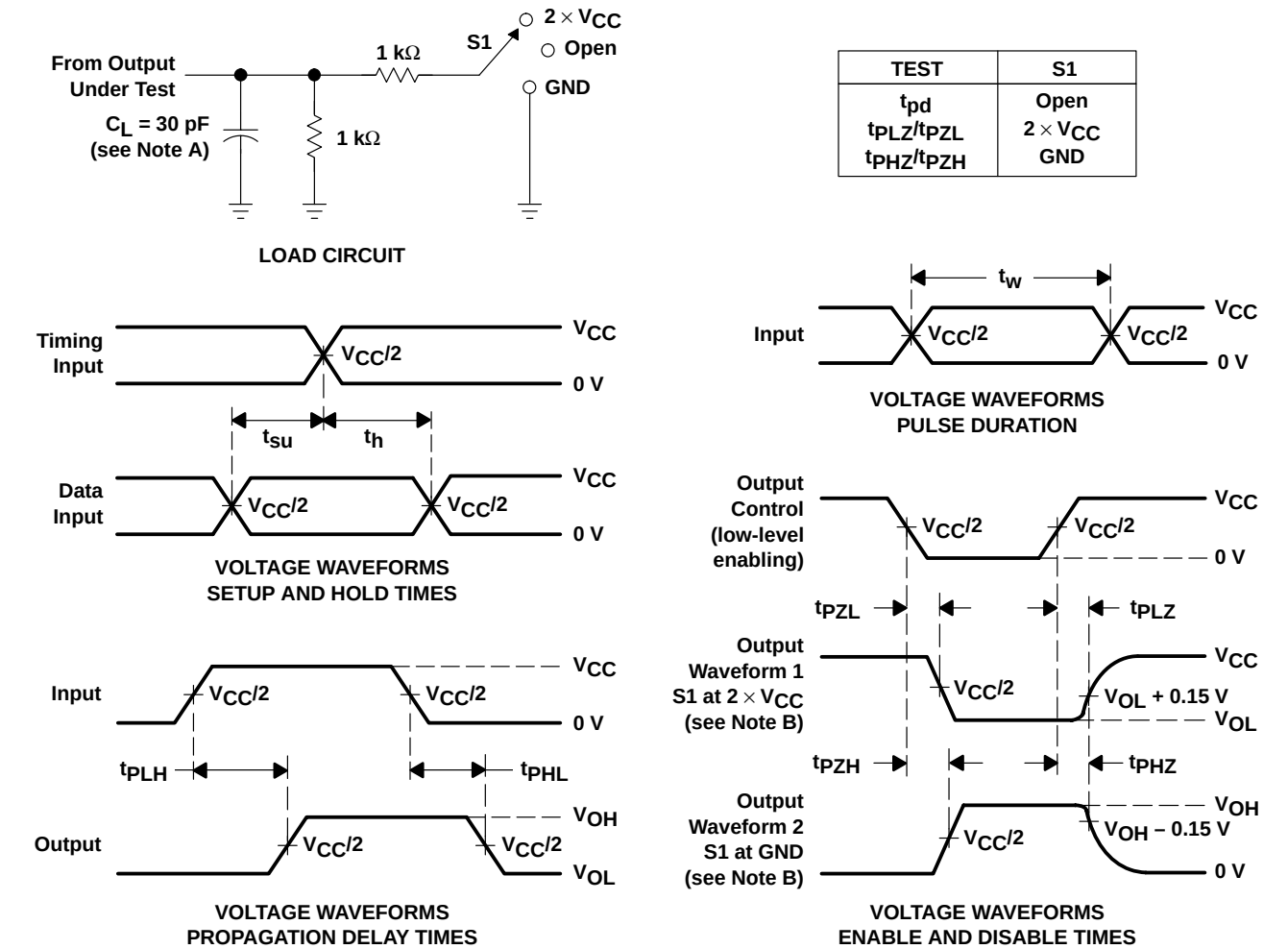
SCES045C – JULY 1995 – REVISED FEBRUARY 1999

operating characteristics, $T_A = 25^{\circ}\text{C}$

PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd} Power dissipation capacitance	Outputs enabled	$C_L = 50\text{ pF}, f = 10\text{ MHz}$	†	16	19	pF
	Outputs disabled		†	4	5	

† This information was not available at the time of publication.

PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8\text{ V}$

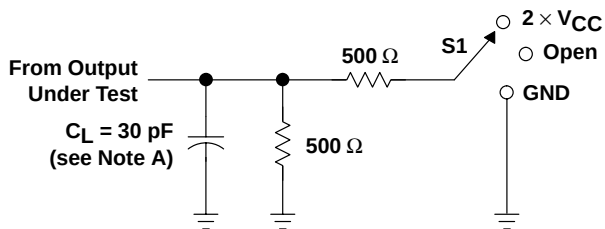


- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

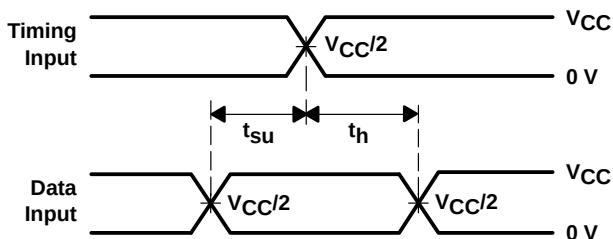
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

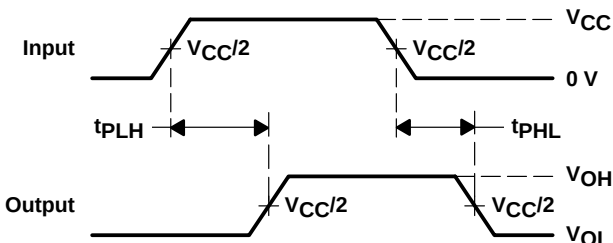


LOAD CIRCUIT

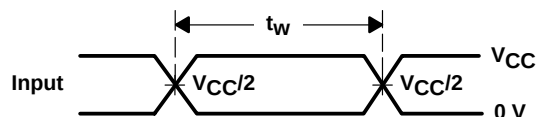
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	$2 \times V_{CC}$
t_{PHZ}/t_{PZH}	GND



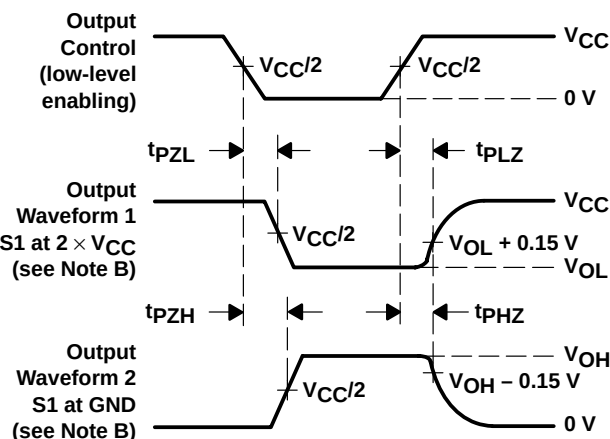
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH16240

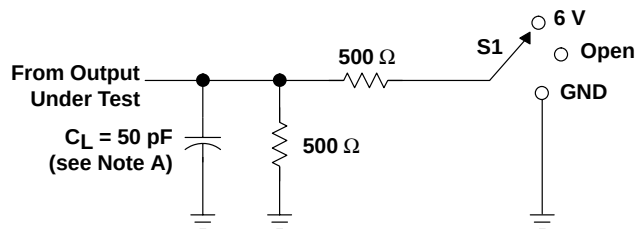
16-BIT BUFFER/DRIVER

WITH 3-STATE OUTPUTS

SCES045C – JULY 1995 – REVISED FEBRUARY 1999

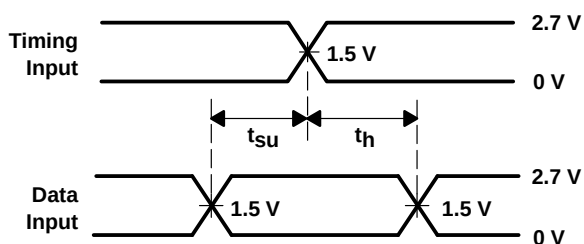
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

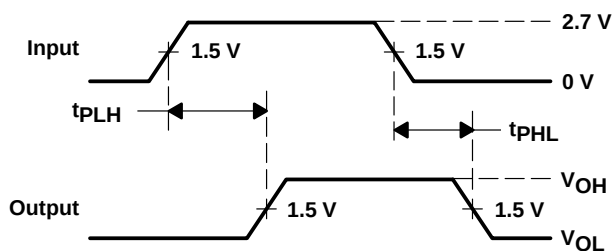


LOAD CIRCUIT

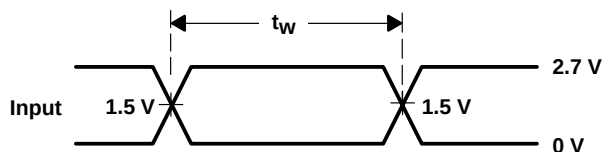
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



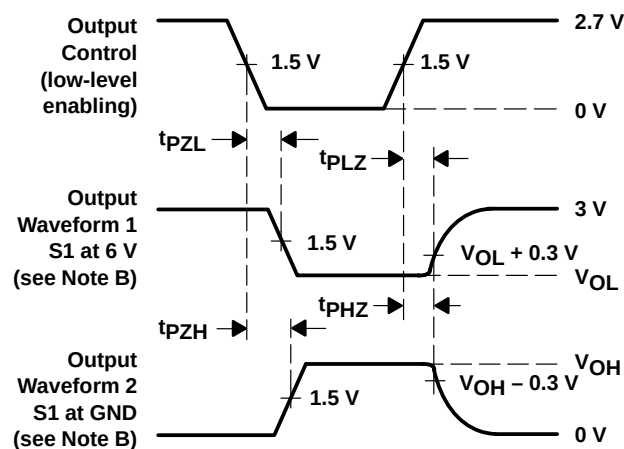
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES: A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
- D. The outputs are measured one at a time with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVC16244A 16-BIT BUFFER/DRIVER WITH 3-STATE OUTPUTS

SCAS250G – JANUARY 1993 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 16-bit buffer/driver is designed for 1.65-V to 3.6-V V_{CC} operation.

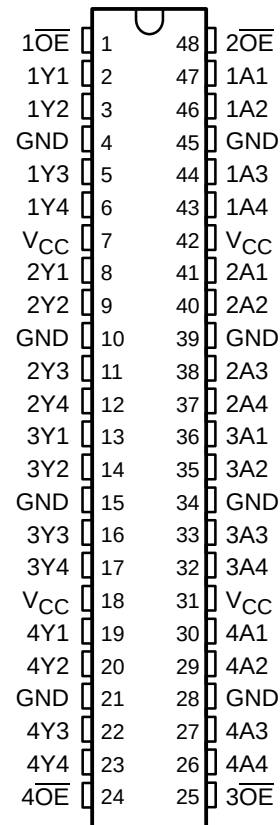
The SN74ALVC16244A is designed specifically to improve the performance and density of 3-state memory-address drivers, clock drivers, and bus-oriented receivers and transmitters.

The device can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. It provides true outputs and symmetrical active-low output-enable ($\overline{OE}$) inputs.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74ALVC16244A is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)



FUNCTION TABLE
(each 4-bit buffer)

INPUTS		OUTPUT
$\overline{OE}$	A	Y
L	H	H
L	L	L
H	X	Z

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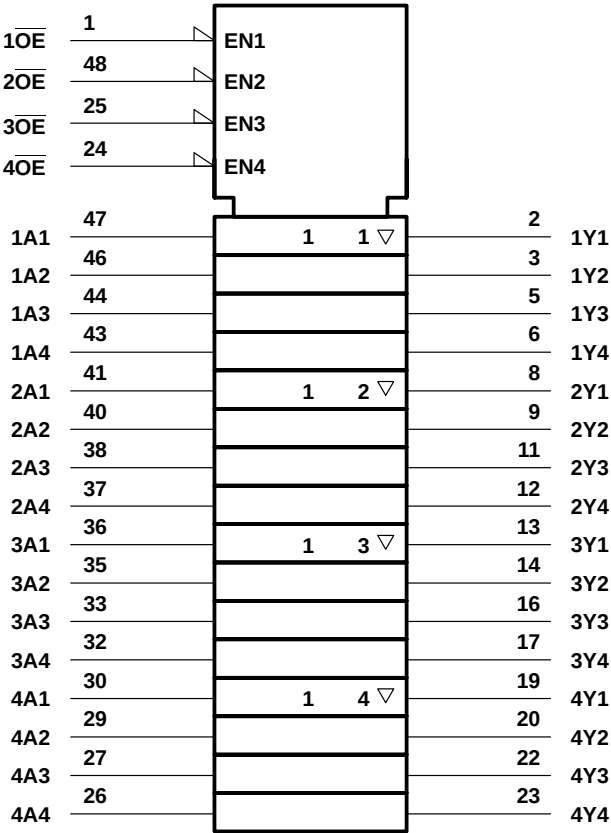
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SN74ALVC16244A
16-BIT BUFFER/DRIVER
WITH 3-STATE OUTPUTS

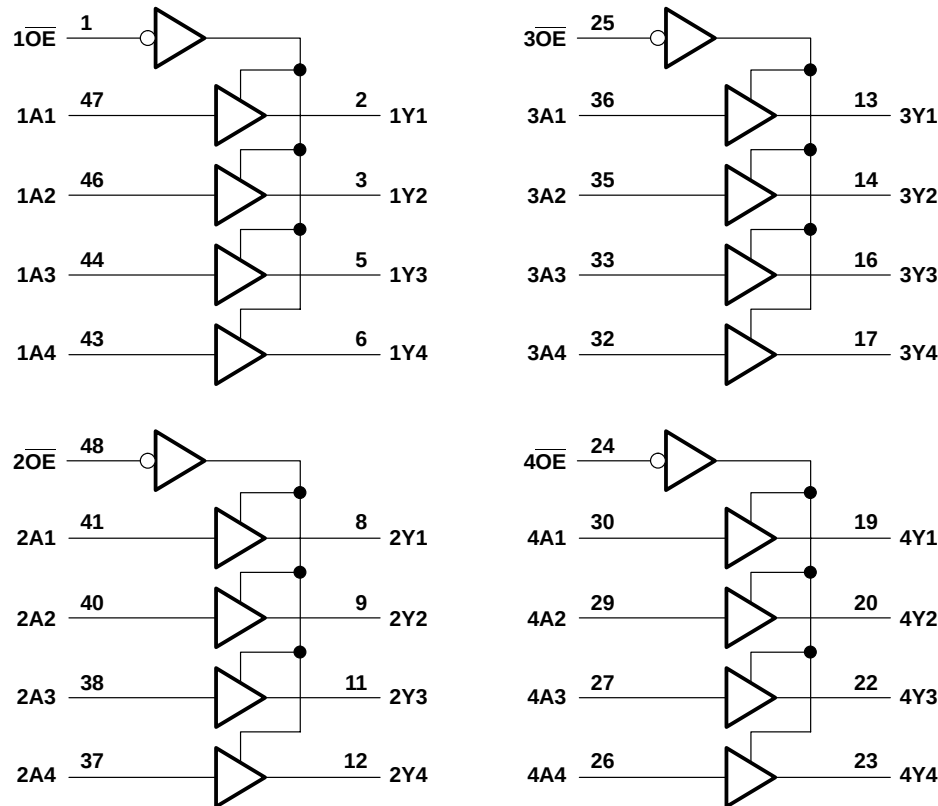
SCAS250G – JANUARY 1993 – REVISED FEBRUARY 1999

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	89°C/W
DL package	94°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

SN74ALVC16244A

16-BIT BUFFER/DRIVER

WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–4	mA
		$V_{CC} = 2.3 \text{ V}$	–12	
		$V_{CC} = 2.7 \text{ V}$	–12	
		$V_{CC} = 3 \text{ V}$	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	4	mA
		$V_{CC} = 2.3 \text{ V}$	12	
		$V_{CC} = 2.7 \text{ V}$	12	
		$V_{CC} = 3 \text{ V}$	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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16-BIT BUFFER/DRIVER
WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
		I _{OL} = 12 mA	2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3			pF
	Data inputs			6			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	Y	‡	1	3.7	3.6		1	3	ns
t _{en}	$\overline{\text{OE}}$	Y	‡	1	5.7	5.4		1	4.4	ns
t _{dis}	$\overline{\text{OE}}$	Y	‡	1	5.2	4.6		1	4.1	ns

[‡] This information was not available at the time of publication.

operating characteristics, T_A = 25°C

PARAMETER		TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
			TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	‡	16	19	pF
		Outputs disabled	‡	4	5	

[‡] This information was not available at the time of publication.



SN74ALVC16244A

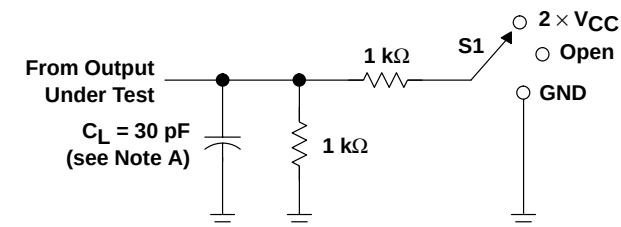
16-BIT BUFFER/DRIVER

WITH 3-STATE OUTPUTS

SCAS250G – JANUARY 1993 – REVISED FEBRUARY 1999

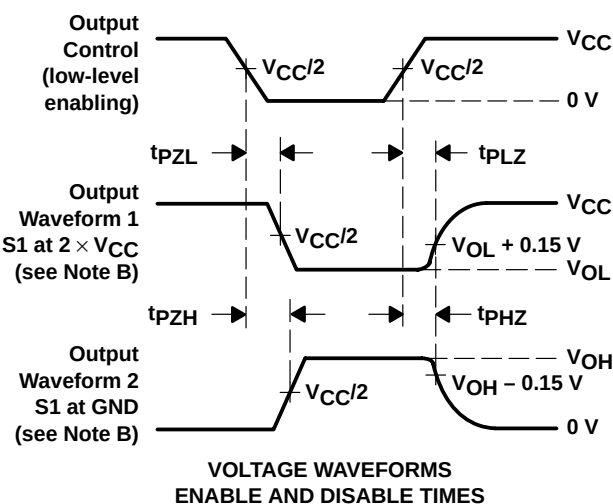
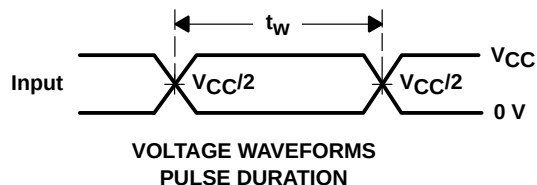
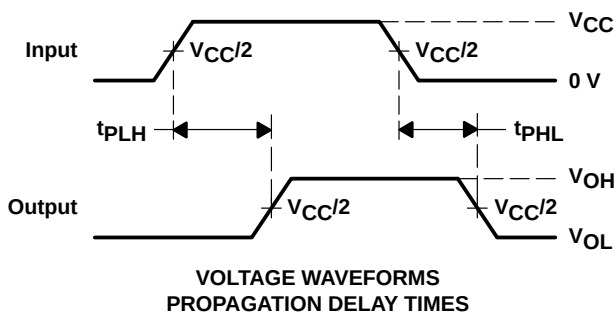
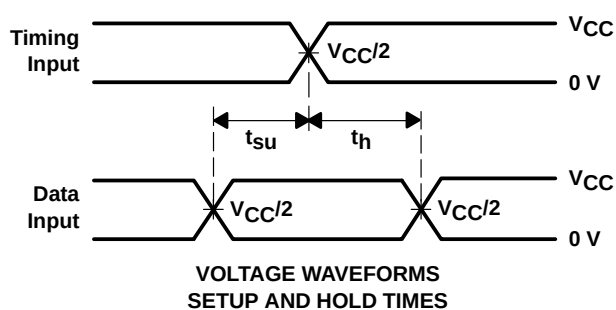
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PHL}	GND

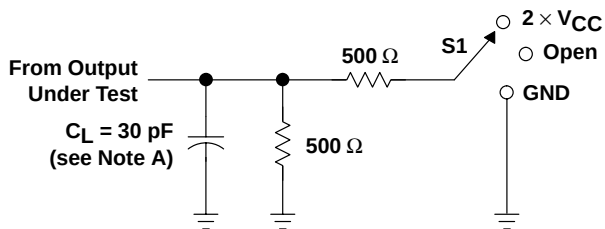


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

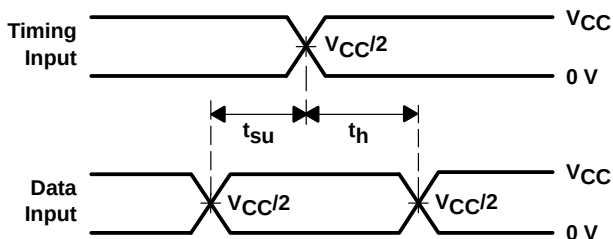
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$$

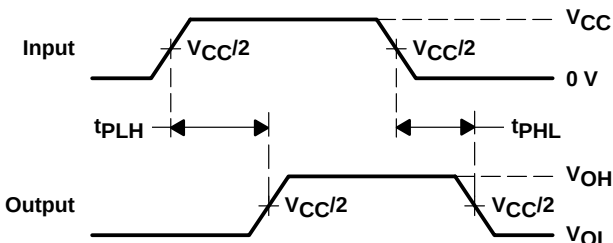


LOAD CIRCUIT

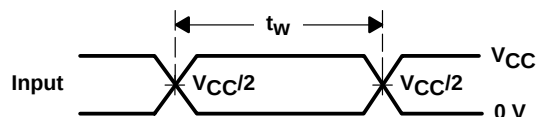
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times$ V_{CC}
t_{PHZ}/t_{PZH}	GND



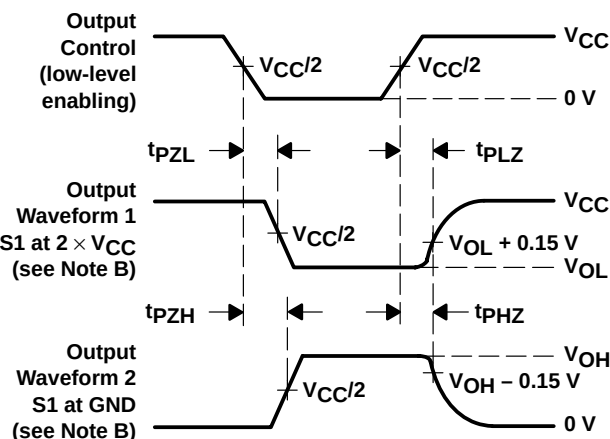
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVC16244A

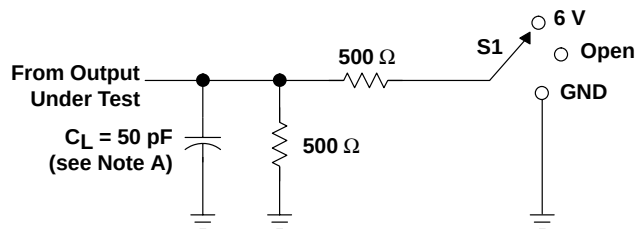
16-BIT BUFFER/DRIVER

WITH 3-STATE OUTPUTS

SCAS250G – JANUARY 1993 – REVISED FEBRUARY 1999

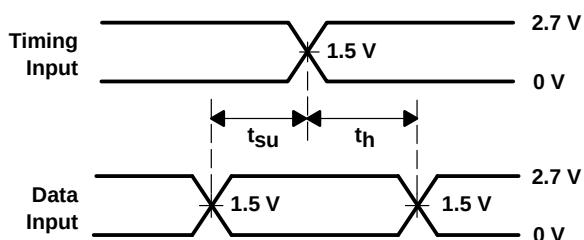
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

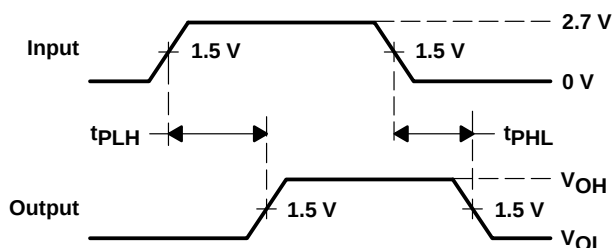


LOAD CIRCUIT

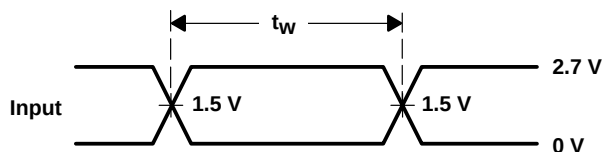
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



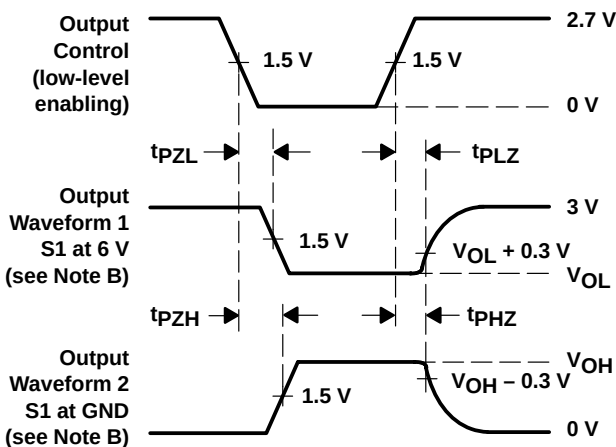
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES: A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
- D. The outputs are measured one at a time with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16244

16-BIT BUFFER/DRIVER WITH 3-STATE OUTPUTS

SCES014E – JULY 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages

description

This 16-bit buffer/driver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16244 is designed specifically to improve the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters.

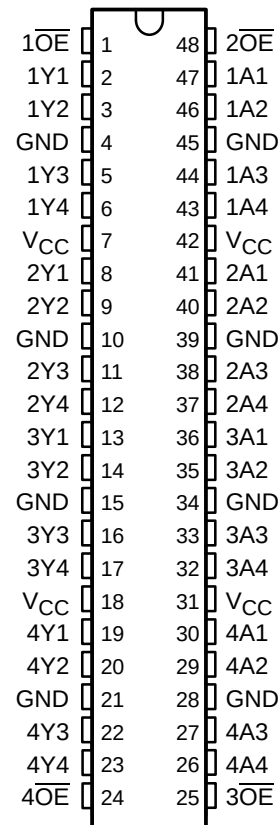
The device can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. It provides true outputs and symmetrical active-low output-enable ($\overline{OE}$) inputs.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16244 is characterized for operation from -40°C to 85°C .

DGG, DGV, OR DL PACKAGE (TOP VIEW)



FUNCTION TABLE
(each 4-bit buffer)

INPUTS		OUTPUT
$\overline{OE}$	A	Y
L	H	H
L	L	L
H	X	Z

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



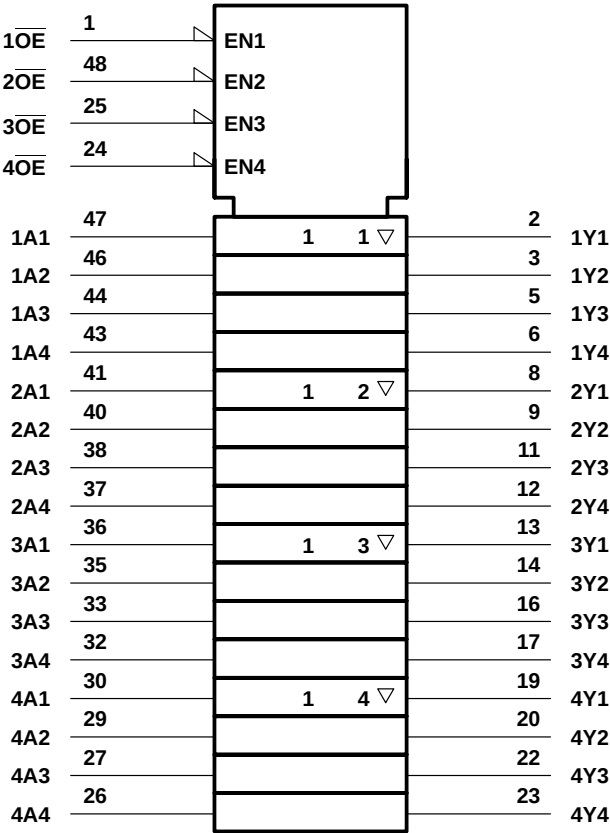
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SN74ALVCH16244
16-BIT BUFFER/DRIVER
WITH 3-STATE OUTPUTS

SCES014E – JULY 1995 – REVISED FEBRUARY 1999

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Figure 1 shows the pin connections for the 74VHC04 hex inverters. The diagram is divided into two columns. The left column shows the first four inverters (1A, 1B, 2A, 2B) and the right column shows the next four inverters (3A, 3B, 4A, 4B). Each inverter is represented by a triangle with a circle at the input and a dot at the output. The input pins are labeled with the pin number and the input signal name (e.g., 1A1, 1A2, 1A3, 1A4). The output pins are labeled with the pin number and the output signal name (e.g., 1Y1, 1Y2, 1Y3, 1Y4). The ground pins are labeled 1OE, 2OE, 3OE, and 4OE.

Pin	Signal	Pin	Signal
1	1OE	25	3OE
47	1A1	36	3A1
46	1A2	35	3A2
44	1A3	33	3A3
43	1A4	32	3A4
2	1Y1	13	3Y1
3	1Y2	14	3Y2
5	1Y3	16	3Y3
6	1Y4	17	3Y4
48	2OE	24	4OE
41	2A1	30	4A1
40	2A2	29	4A2
38	2A3	27	4A3
37	2A4	26	4A4
8	2Y1	19	4Y1
9	2Y2	20	4Y2
11	2Y3	22	4Y3
12	2Y4	23	4Y4

NOTES:

1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

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16-BIT BUFFER/DRIVER
WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–4	mA
		$V_{CC} = 2.3 \text{ V}$	–12	
		$V_{CC} = 2.7 \text{ V}$	–12	
		$V_{CC} = 3 \text{ V}$	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	4	mA
		$V_{CC} = 2.3 \text{ V}$	12	
		$V_{CC} = 2.7 \text{ V}$	12	
		$V_{CC} = 3 \text{ V}$	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

SN74ALVCH16244
16-BIT BUFFER/DRIVER
WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = −100 μA	1.65 V to 3.6 V	V _{CC} −0.2			V
		I _{OH} = −4 mA	1.65 V	1.2			
		I _{OH} = −6 mA	2.3 V	2			
	I _{OH} = −12 mA		2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
	I _{OH} = −24 mA	3 V	2				
V _{OL}		I _{OL} = 100 μA	1.65 V to 3.6 V			0.2	V
		I _{OL} = 4 mA	1.65 V			0.45	
		I _{OL} = 6 mA	2.3 V			0.4	
	I _{OL} = 12 mA		2.3 V			0.7	
			2.7 V			0.4	
	I _{OL} = 24 mA	3 V			0.55		
I _I	V _I = V _{CC} or GND		3.6 V			±5	μA
I _I (hold)		V _I = 0.58 V	1.65 V	25			μA
		V _I = 1.07 V	1.65 V	−25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	−45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	−75			
		V _I = 0 to 3.6 V [‡]	3.6 V			±500	
I _{OZ}	V _O = V _{CC} or GND		3.6 V			±10	μA
I _{CC}	V _I = V _{CC} or GND, I _O = 0		3.6 V			40	μA
ΔI _{CC}		One input at V _{CC} − 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V			750	μA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3		pF	
	Data inputs			6			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7		pF	

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	Y	§	1	3.7	3.6		1	3	ns
t _{en}	$\overline{\text{OE}}$	Y	§	1	5.7	5.4		1	4.4	ns
t _{dis}	$\overline{\text{OE}}$	Y	§	1	5.2	4.6		1	4.1	ns

§ This information was not available at the time of publication.



SN74ALVCH16244
16-BIT BUFFER/DRIVER
WITH 3-STATE OUTPUTS

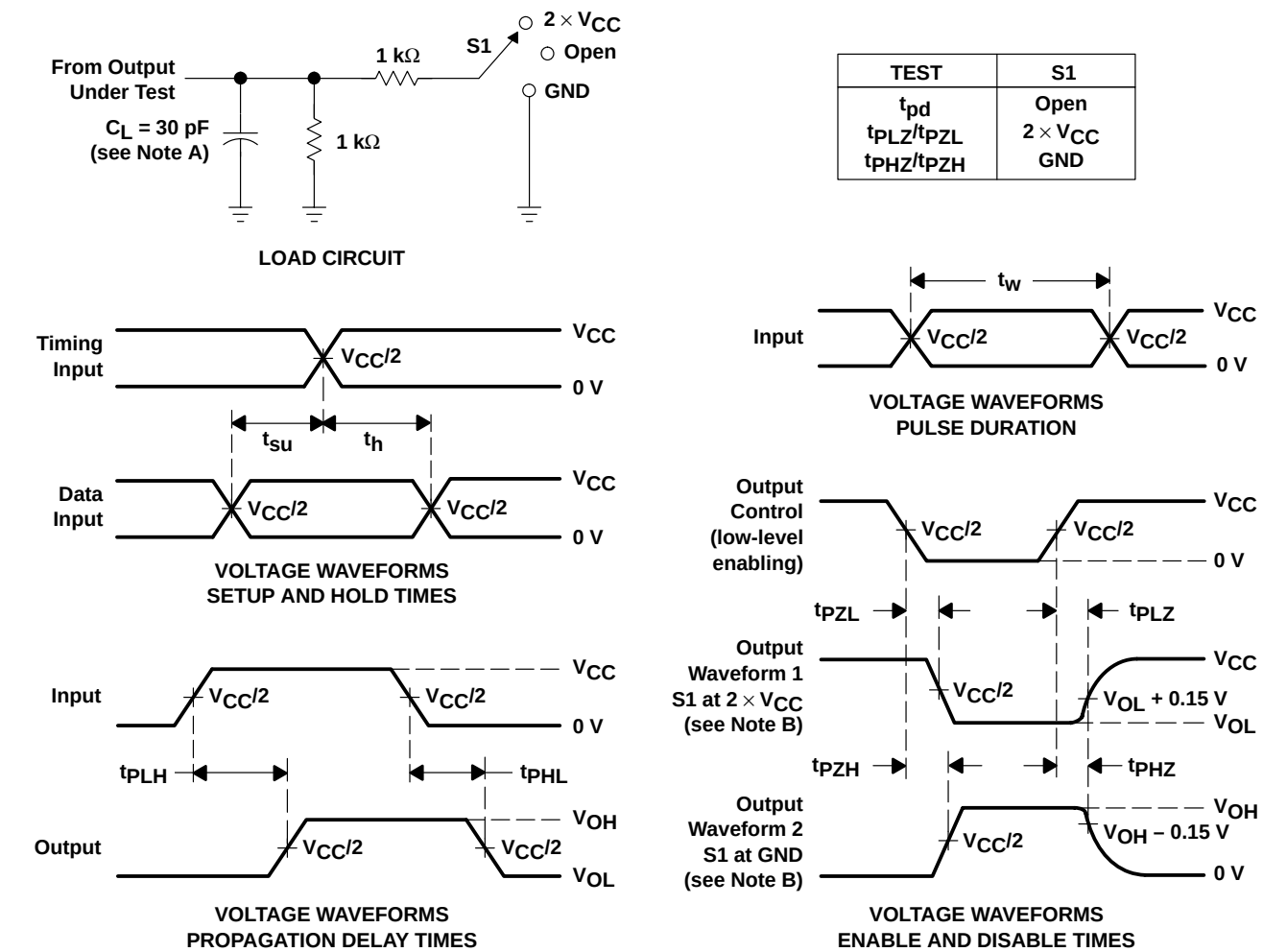
SCES014E – JULY 1995 – REVISED FEBRUARY 1999

operating characteristics, $T_A = 25^{\circ}\text{C}$

PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd} Power dissipation capacitance	Outputs enabled	$C_L = 50\text{ pF}, f = 10\text{ MHz}$	†	16	19	pF
	Outputs disabled		†	4	5	

† This information was not available at the time of publication.

PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8\text{ V}$

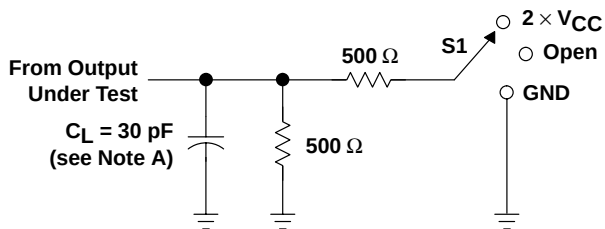


- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r ≤ 2 ns, t_f ≤ 2 ns.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{pLZ} and t_{pHZ} are the same as t_{dis}.
 - F. t_{pZL} and t_{pZH} are the same as t_{en}.
 - G. t_{PLH} and t_{PHL} are the same as t_{pd}.

Figure 1. Load Circuit and Voltage Waveforms

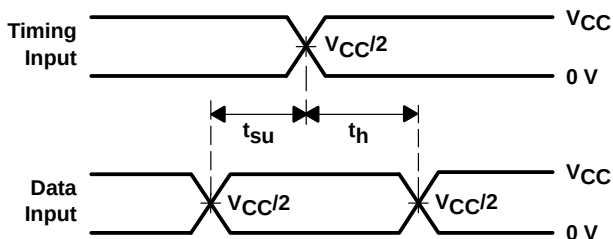
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

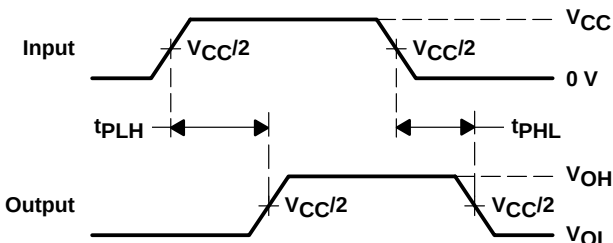


LOAD CIRCUIT

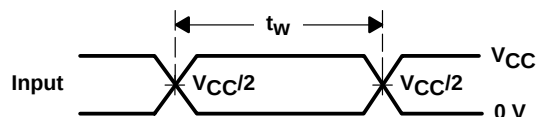
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



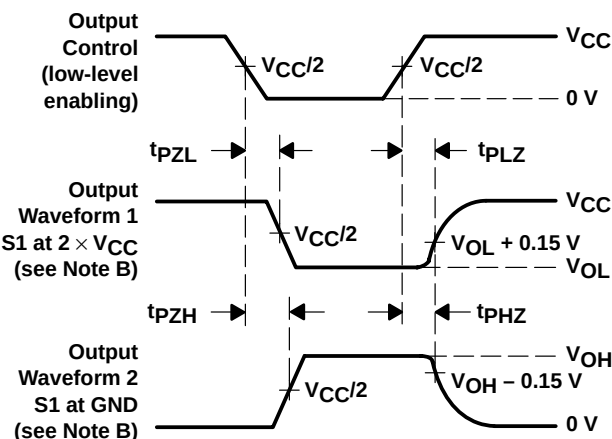
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES: A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
- D. The outputs are measured one at a time with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH16244

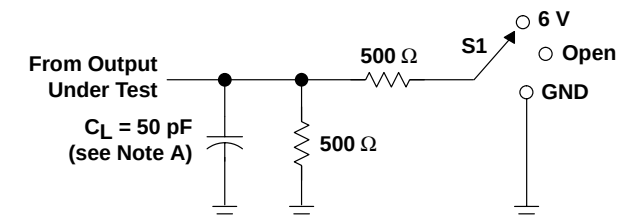
16-BIT BUFFER/DRIVER

WITH 3-STATE OUTPUTS

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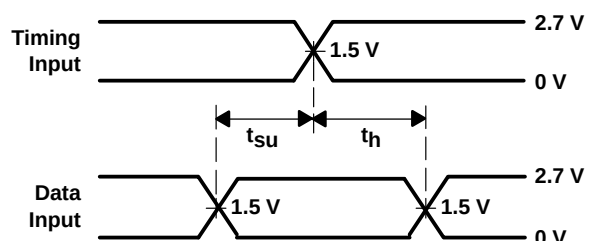
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

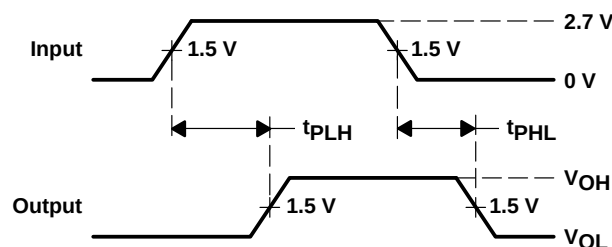


LOAD CIRCUIT

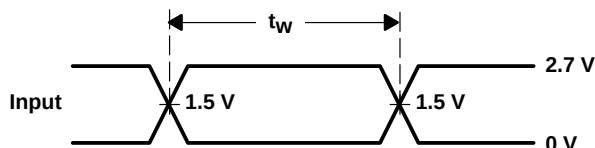
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



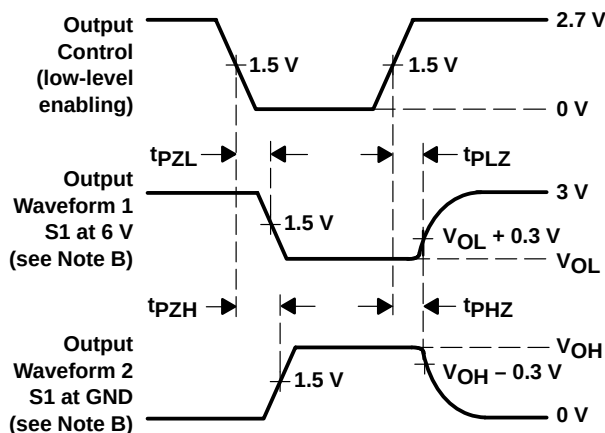
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16245

16-BIT BUS TRANSCEIVER WITH 3-STATE OUTPUTS

SCES015F – JULY 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages

description

This 16-bit (dual-octal) noninverting bus transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16245 is designed for asynchronous communication between data buses. The control-function implementation minimizes external timing requirements.

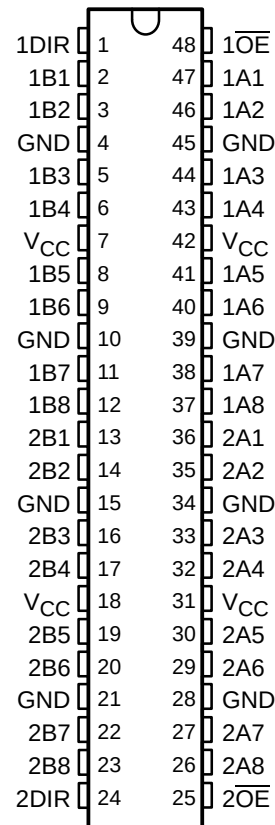
This device can be used as two 8-bit transceivers or one 16-bit transceiver. It allows data transmission from the A bus to the B bus or from the B bus to the A bus, depending on the logic level at the direction-control (DIR) input. The output-enable ($\overline{OE}$) input can be used to disable the device so that the buses are effectively isolated.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16245 is characterized for operation from -40°C to 85°C .

DGG, DGV, OR DL PACKAGE
(TOP VIEW)



FUNCTION TABLE
(each 8-bit section)

INPUTS		OPERATION
$\overline{OE}$	DIR	
L	L	B data to A bus
L	H	A data to B bus
H	X	Isolation

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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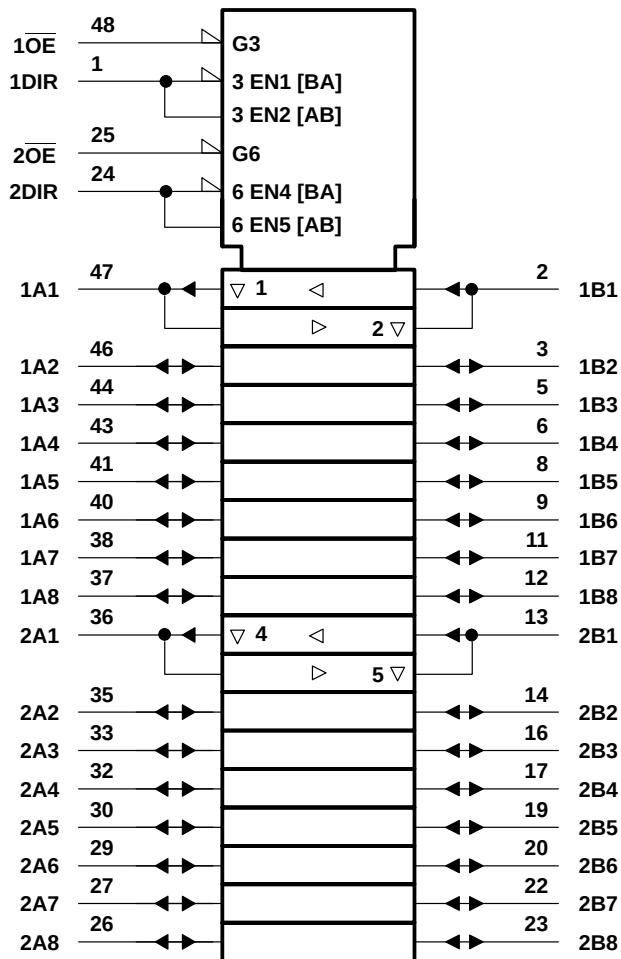
SN74ALVCH16245

16-BIT BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

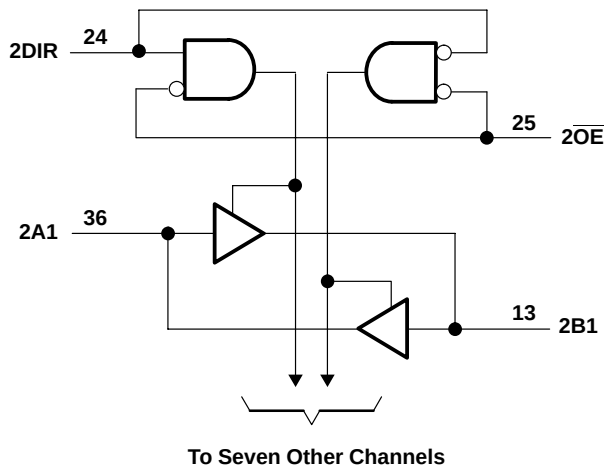
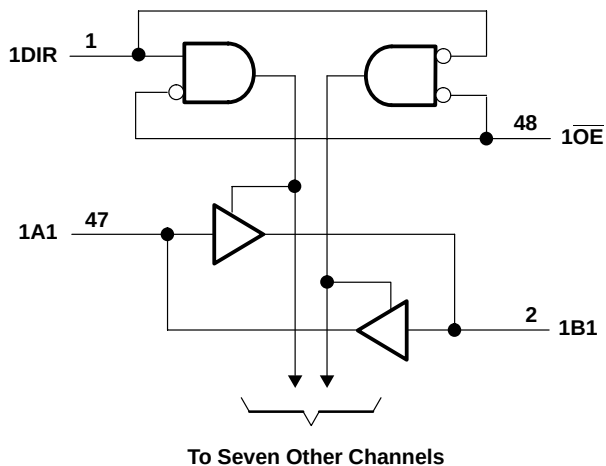
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logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



Supply voltage range, V_{CC}		-0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)		-0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)		-0.5 V to $V_{CC} + 0.5$ V
Output-voltage range, V_O (see Notes 1 and 2)		-0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)		-50 mA
Output clamp current, I_{OK} ($V_O < 0$)		-50 mA
Continuous output current, I_O		± 50 mA
Continuous current through each V_{CC} or GND		± 100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package		89°C/W
DGV package		93°C/W
DL package		94°C/W

NOTES:

1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JEDEC 51.

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate		10		ns/V
T _A	Operating free-air temperature		−40	85	°C



SN74ALVCH16245
16-BIT BUS TRANSCEIVER
WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ} [§]	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V		4	pF
C _{i0}	A or B ports	V _O = V _{CC} or GND	3.3 V		8	pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A or B	B or A	¶	1	3.7	3.6		1	3	ns
t _{en}	OE	A or B	¶	1	5.7	5.4		1	4.4	ns
t _{dis}	OE	A or B	¶	1	5.2	4.6		1	4.1	ns

¶ This information was not available at the time of publication.



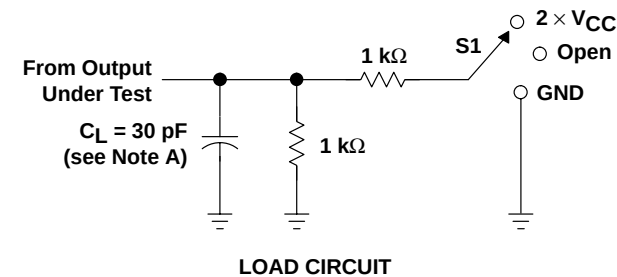
operating characteristics, $T_A = 25^\circ \text{C}$

PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8 \text{ V}$	$V_{CC} = 2.5 \text{ V}$	$V_{CC} = 3.3 \text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd} Power dissipation capacitance	Outputs enabled	$C_L = 50 \text{ pF}, f = 10 \text{ MHz}$	†	22	29	pF
	Outputs disabled		†	4	5	

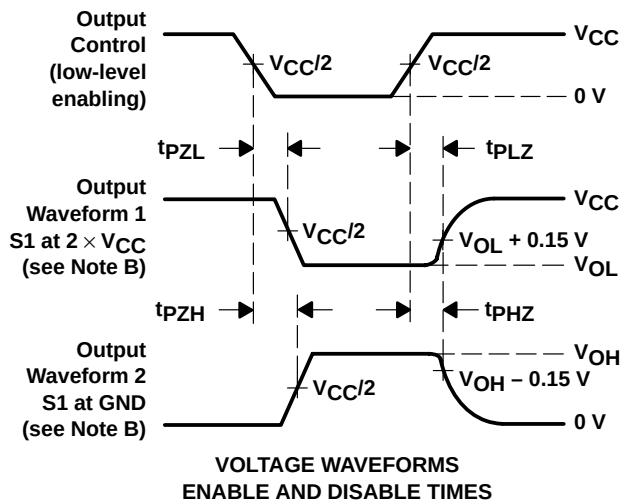
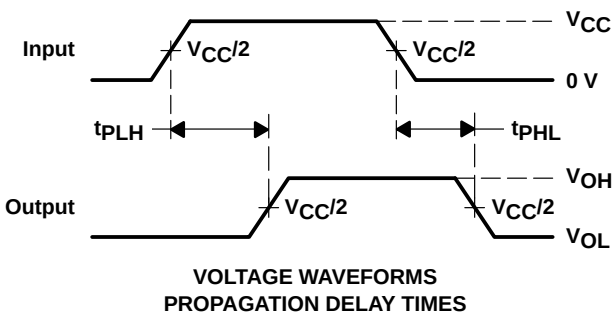
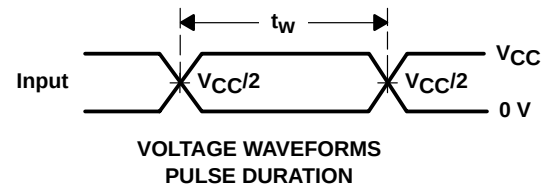
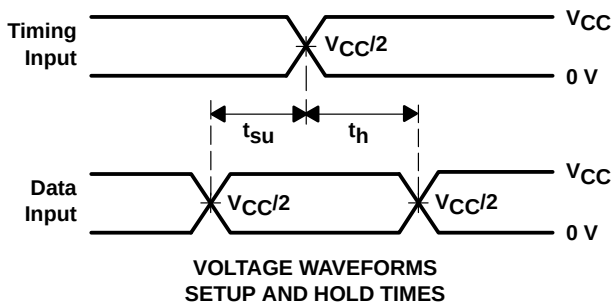
† This information was not available at the time of publication.

PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH16245

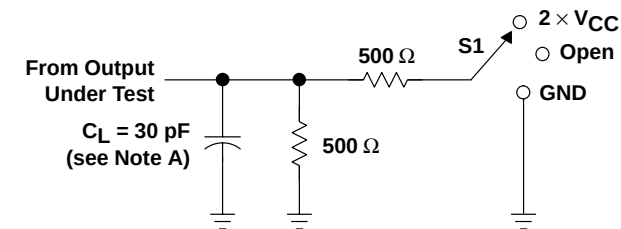
16-BIT BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

SCES015F – JULY 1995 – REVISED FEBRUARY 1999

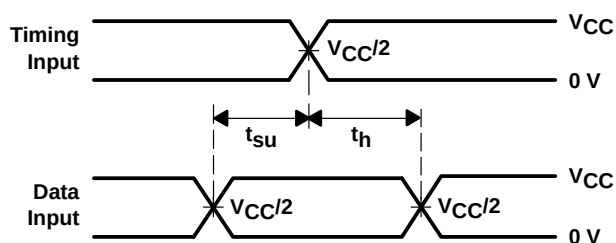
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

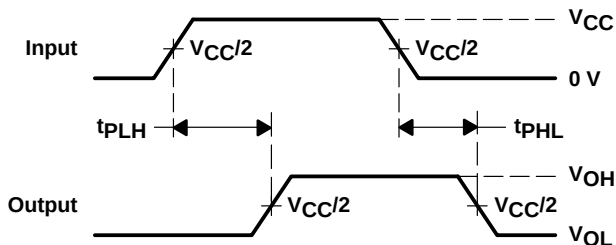


LOAD CIRCUIT

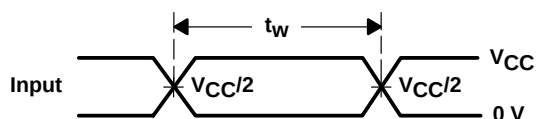
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



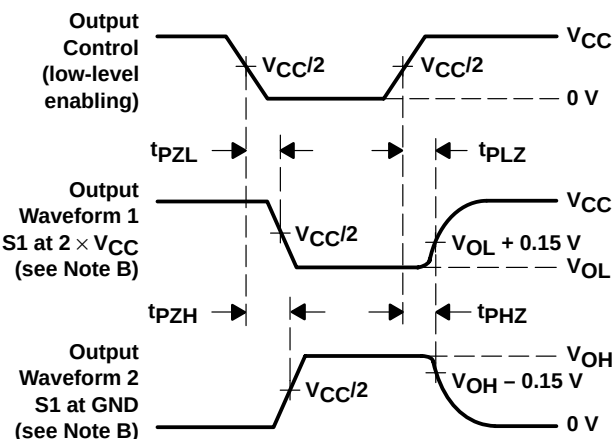
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



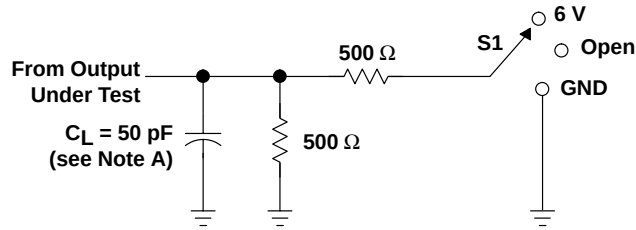
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

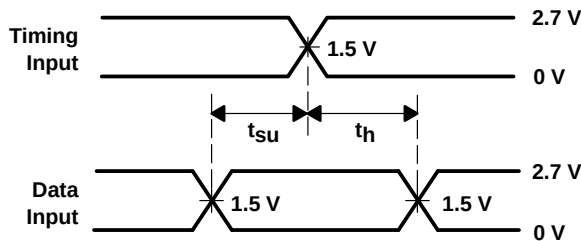
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

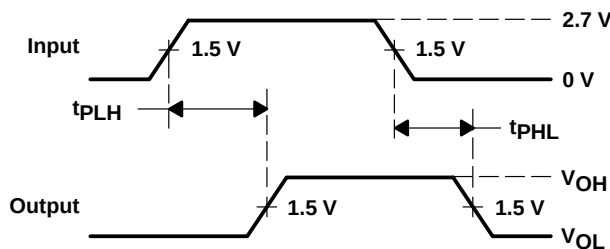


LOAD CIRCUIT

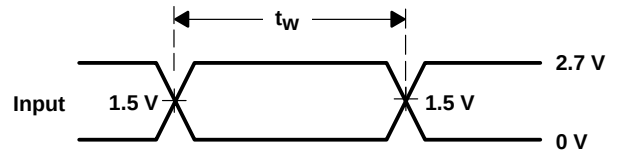
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



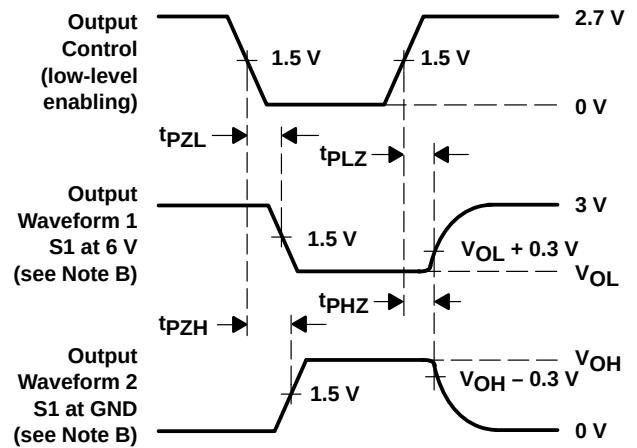
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16260

12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 12-bit to 24-bit multiplexed D-type latch is designed for 1.65-V to 3.6-V_{CC} operation.

The SN74ALVCH16260 is used in applications in which two separate data paths must be multiplexed onto, or demultiplexed from, a single data path. Typical applications include multiplexing and/or demultiplexing address and data information in microprocessor or bus-interface applications. This device also is useful in memory-interleaving applications.

Three 12-bit I/O ports (A1–A12, 1B1–1B12, and 2B1–2B12) are available for address and/or data transfer. The output-enable ($\overline{OE1B}$, $\overline{OE2B}$, and $\overline{OE1A}$) inputs control the bus transceiver functions. The $\overline{OE1B}$ and $\overline{OE2B}$ control signals also allow bank control in the A-to-B direction.

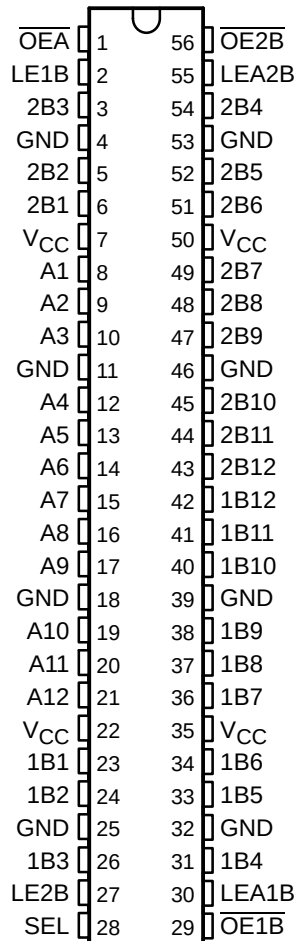
Address and/or data information can be stored using the internal storage latches. The latch-enable (LE1B, LE2B, LEA1B, and LEA2B) inputs are used to control data storage. When the latch-enable input is high, the latch is transparent. When the latch-enable input goes low, the data present at the inputs is latched and remains latched until the latch-enable input is returned high.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16260 is characterized for operation from –40°C to 85°C.

DGG OR DL PACKAGE
(TOP VIEW)



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12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH
WITH 3-STATE OUTPUTS

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Function Tables

B TO A ($\overline{OE\overline{B}} = H$)

INPUTS						OUTPUT A
1B	2B	SEL	LE1B	LE2B	$\overline{OE\overline{A}}$	
H	X	H	H	X	L	H
L	X	H	H	X	L	L
X	X	H	L	X	L	A ₀
X	H	L	X	H	L	H
X	L	L	X	H	L	L
X	X	L	X	L	L	A ₀
X	X	X	X	X	H	Z

A TO B ($\overline{OE\overline{A}} = H$)

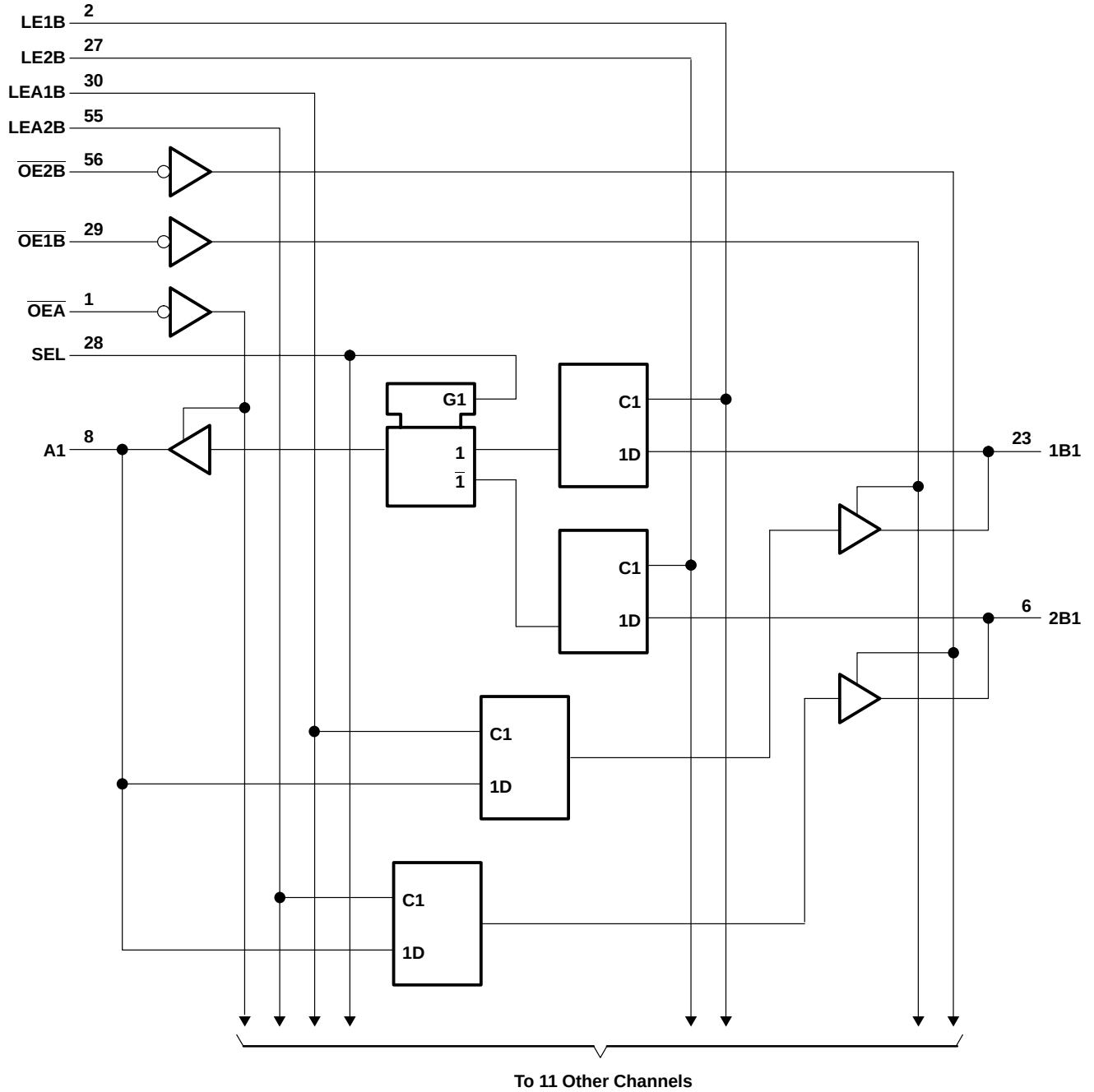
INPUTS					OUTPUTS	
A	LEA1B	LEA2B	$\overline{OE1\overline{B}}$	$\overline{OE2\overline{B}}$	1B	2B
H	H	H	L	L	H	H
L	H	H	L	L	L	L
H	H	L	L	L	H	2B ₀
L	H	L	L	L	L	2B ₀
H	L	H	L	L	1B ₀	H
L	L	H	L	L	1B ₀	L
X	L	L	L	L	1B ₀	2B ₀
X	X	X	H	H	Z	Z
X	X	X	L	H	Active	Z
X	X	X	H	L	Z	Active
X	X	X	L	L	Active	Active

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12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH WITH 3-STATE OUTPUTS

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logic diagram (positive logic)



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12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH

WITH 3-STATE OUTPUTS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH
WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
		I _{OL} = 12 mA	2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V			±5	µA
I _{I(hold)}		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V			±500	
I _{OZ} [§]		V _O = V _{CC} or GND	3.6 V			±10	µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V			40	µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V			750	µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V			3.5	pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V			9	pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t _W	Pulse duration, LE1B, LE2B, LEA1B, or LEA2B high	¶		3.3		3.3		3.3		ns
t _{su}	Setup time, data before LE1B, LE2B, LEA1B, or LEA2B	¶		1.4		1.1		1.1		ns
t _h	Hold time, data after LE1B, LE2B, LEA1B, or LEA2B	¶		1.6		1.9		1.5		ns

¶ This information was not available at the time of publication.



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12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A or B	B or A	†	1	5.4	5.1		1.2	4.3	ns
	LE	A or B	†	1	5.6	5.2		1	4.4	
	SEL	A	†	1	6.9	6.6		1.1	5.6	
t _{en}	$\overline{OE}$	A or B	†	1	6.7	6.4		1	5.4	ns
t _{dis}	$\overline{OE}$	A or B	†	1	5.7	5		1.3	4.6	ns

† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	All outputs enabled	C _L = 50 pF, f = 10 MHz	†	37	41	pF
		All outputs disabled		†	4	7	

† This information was not available at the time of publication.

SN74ALVCH16260

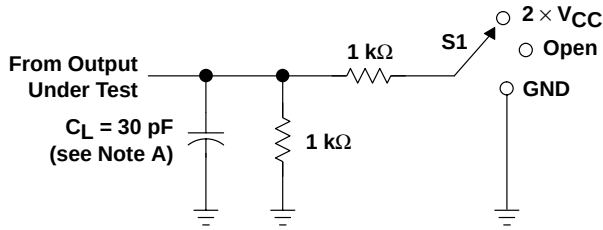
12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH

WITH 3-STATE OUTPUTS

SCES046E – JULY 1995 – REVISED FEBRUARY 1999

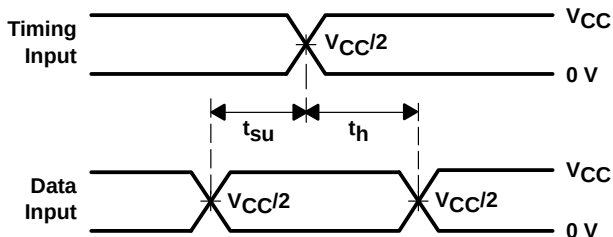
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$

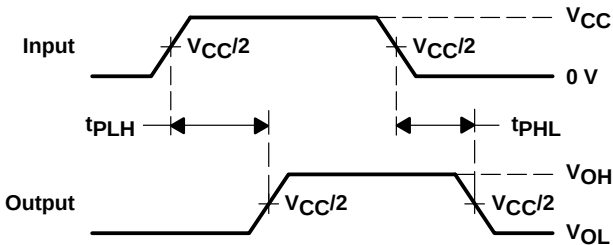


LOAD CIRCUIT

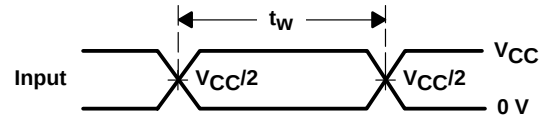
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



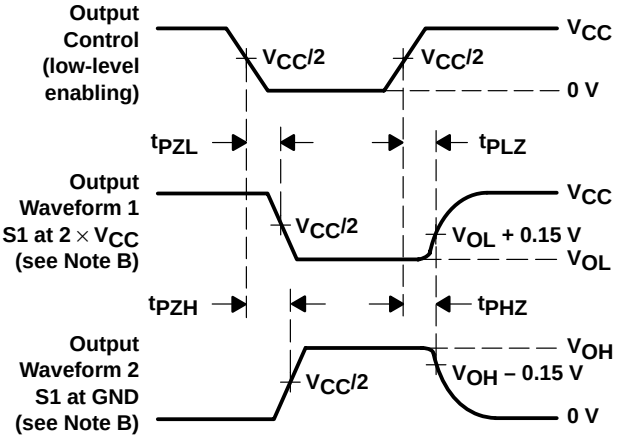
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
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 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH16260

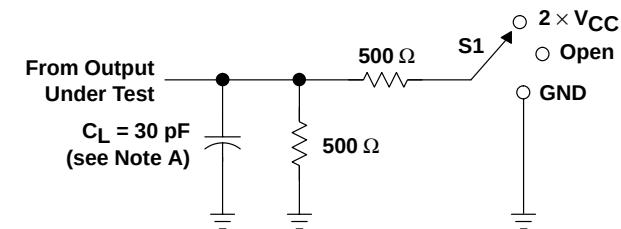
12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH

WITH 3-STATE OUTPUTS

SCES046E – JULY 1995 – REVISED FEBRUARY 1999

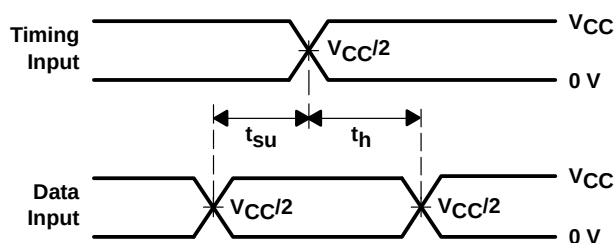
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

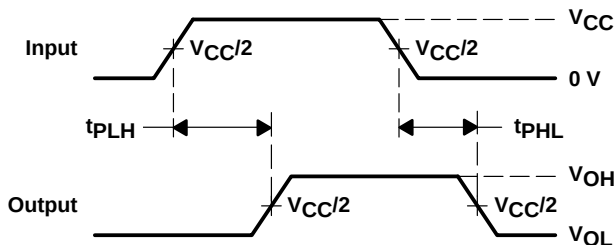


LOAD CIRCUIT

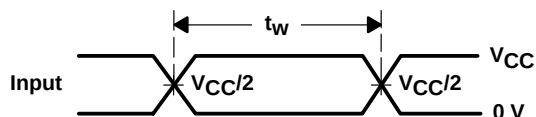
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



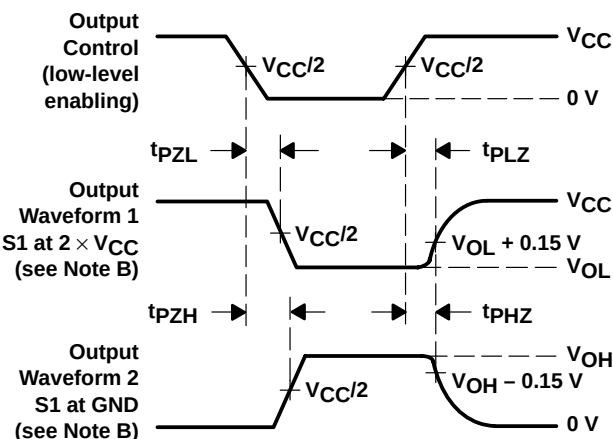
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
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 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH16260

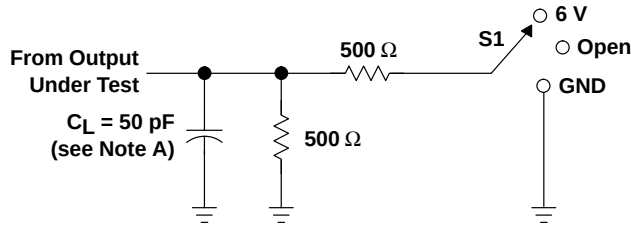
12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH

WITH 3-STATE OUTPUTS

SCES046E – JULY 1995 – REVISED FEBRUARY 1999

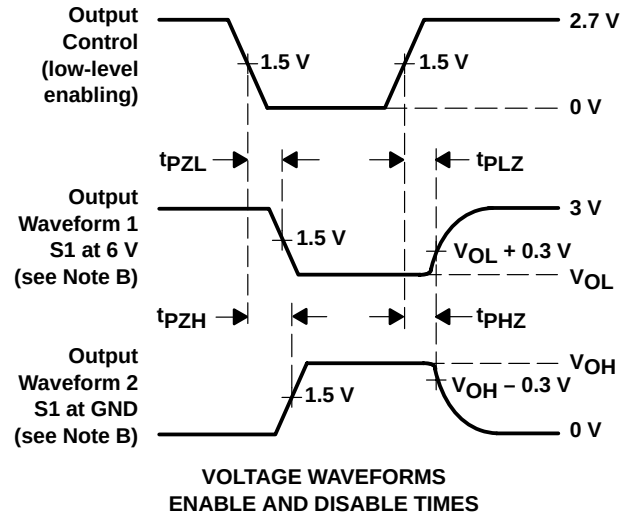
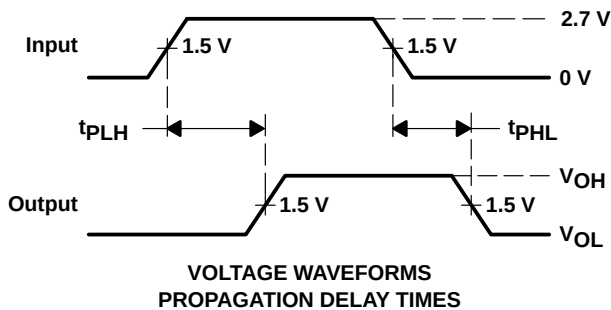
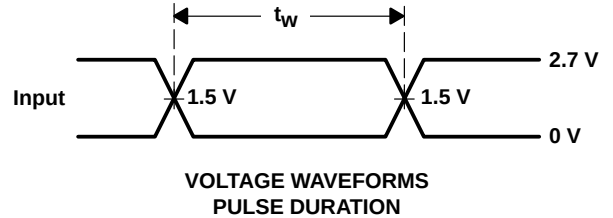
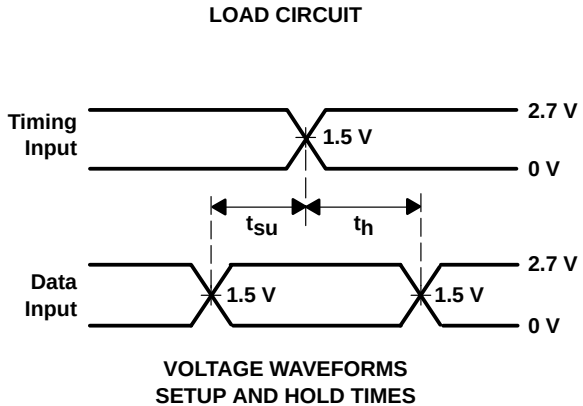
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V}$ AND $3.3 \text{ V} \pm 0.3 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dLZ} .
 - t_{PZL} and t_{PZH} are the same as t_{dLH} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16269

12-BIT TO 24-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

SCES019H – JULY 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 12-bit to 24-bit registered bus exchanger is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16269 is used in applications in which two separate ports must be multiplexed onto, or demultiplexed from, a single port. The device is particularly suitable as an interface between synchronous DRAMs and high-speed microprocessors.

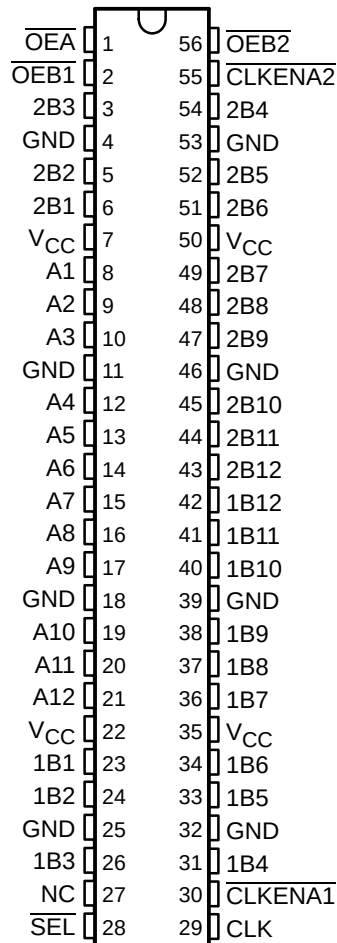
Data is stored in the internal B-port registers on the low-to-high transition of the clock (CLK) input when the appropriate clock-enable ($\overline{CLKENA}$) inputs are low. Proper control of these inputs allows two sequential 12-bit words to be presented as a 24-bit word on the B port. For data transfer in the B-to-A direction, a single storage register is provided. The select ($\overline{SEL}$) line selects 1B or 2B data for the A outputs. The register on the A output permits the fastest possible data transfer, thus extending the period during which the data is valid on the bus. The control terminals are registered so that all transactions are synchronous with CLK. Data flow is controlled by the active-low output enables ($\overline{OEA}$, $\overline{OEB1}$, $\overline{OEB2}$).

To ensure the high-impedance state during power up or power down, a clock pulse should be applied as soon as possible and $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver. Due to $\overline{OE}$ being routed through a register, the active state of the outputs cannot be determined prior to the arrival of the first clock pulse.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16269 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)



NC – No internal connection

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SN74ALVCH16269
12-BIT TO 24-BIT REGISTERED BUS EXCHANGER
WITH 3-STATE OUTPUTS

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Function Tables

OUTPUT ENABLE

INPUTS			OUTPUTS	
CLK	$\overline{OE}A$	$\overline{OE}B$	A	1B, 2B
↑	H	H	Z	Z
↑	H	L	Z	Active
↑	L	H	Active	Z
↑	L	L	Active	Active

A-TO-B STORAGE ($\overline{OE}B = L$)

INPUTS				OUTPUTS	
$\overline{CLK}ENA1$	$\overline{CLK}ENA2$	CLK	A	1B	2B
H	H	X	X	1B ₀ [†]	2B ₀ [†]
L	X	↑	L	L	X
L	X	↑	H	H	X
X	L	↑	L	X	L
X	L	↑	H	X	H

† Output level before the indicated steady-state input conditions were established

B-TO-A STORAGE ($\overline{OE}A = L$)

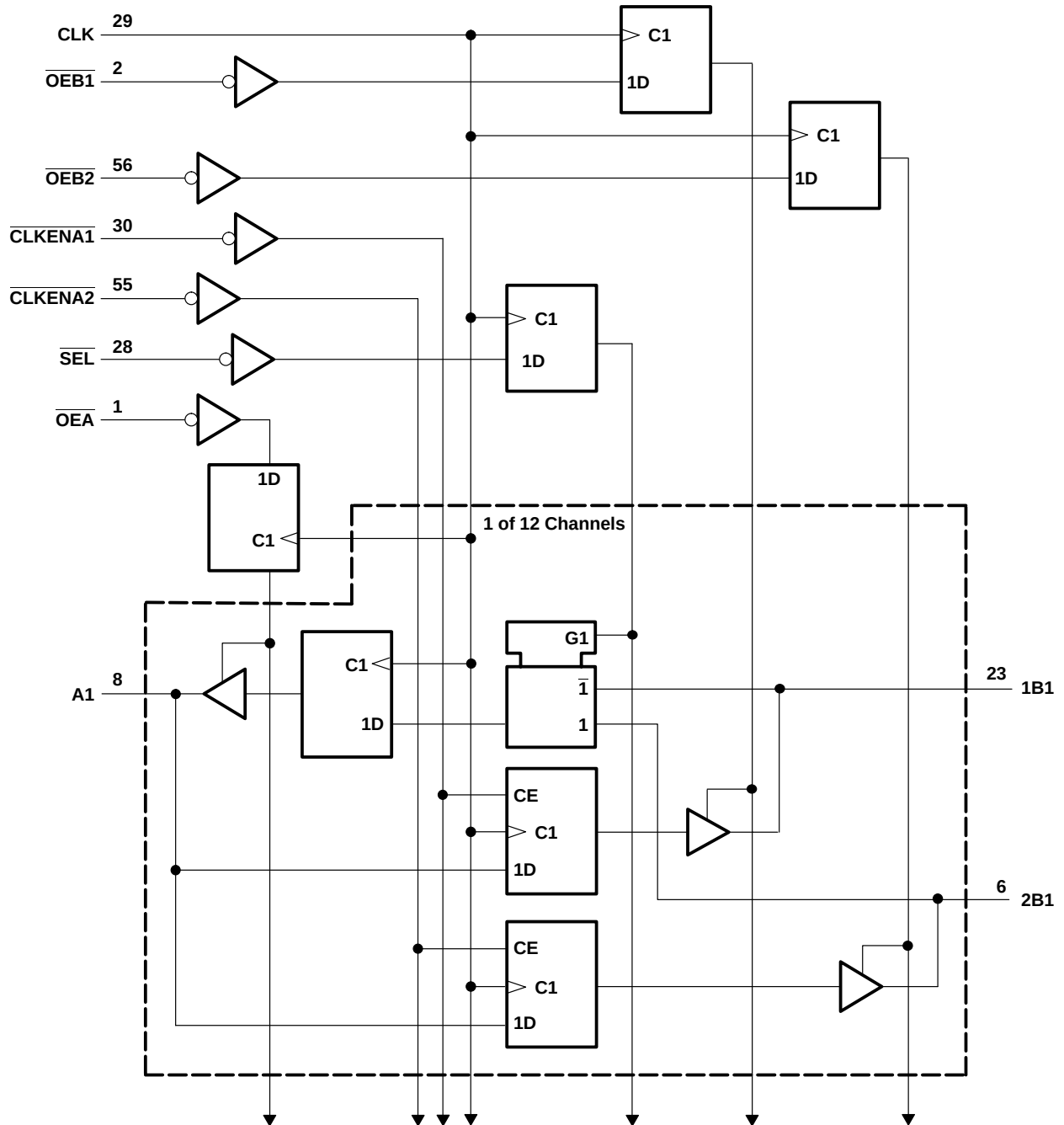
INPUTS				OUTPUT
CLK	$\overline{SEL}$	1B	2B	A
X	H	X	X	A ₀ [†]
X	L	X	X	A ₀ [†]
↑	H	L	X	L
↑	H	H	X	H
↑	L	X	L	L
↑	L	X	H	H

† Output level before the indicated steady-state input conditions were established

SN74ALVCH16269
12-BIT TO 24-BIT REGISTERED BUS EXCHANGER
WITH 3-STATE OUTPUTS

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logic diagram (positive logic)



SN74ALVCH16269

12-BIT TO 24-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DGV package	86°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



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12-BIT TO 24-BIT REGISTERED BUS EXCHANGER
WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
		I _{OL} = 12 mA	2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ} [§]		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3.5			pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V	9			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.



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12-BIT TO 24-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT		
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX			
f _{clock}	Clock frequency	†		135		135		135		MHz		
t _w	Pulse duration, CLK high or low	†		3.3		3.3		3.3		ns		
t _{su}	Setup time	A data before CLK↑		†		2		2		1.7		ns
		B data before CLK↑		†		2.2		2.1		1.8		
		SEL before CLK↑		†		1.6		1.6		1.3		
		CLKENA1 or CLKENA2 before CLK↑		†		1		1.2		0.9		
		OE before CLK↑		†		1.5		1.6		1.3		
t _h	Hold time	A data after CLK↑		†		0.7		0.6		0.6		ns
		B data after CLK↑		†		0.7		0.6		0.6		
		SEL after CLK↑		†		1.1		0.7		0.7		
		CLKENA1 or CLKENA2 after CLK↑		†		1		0.8		1.1		
		OE after CLK↑		†		0.8		0.8		0.8		

† This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 1.8\text{ V}$		$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f_{max}			†		135		135		135		MHz
t_{pd}	CLK	B	†		1	8.2	7.3		1	6.2	ns
		A	†		1	6.4	5.8		1	5	
t_{en}	CLK	B	†		1	7.9	6.7		1	6.1	ns
		A	†		1	7.6	6.2		1	5.9	
t_{dis}	CLK	B	†		1	8.1	6.9		1	6.1	ns
		A	†		1	7.5	6.8		1	5.6	

† This information was not available at the time of publication.

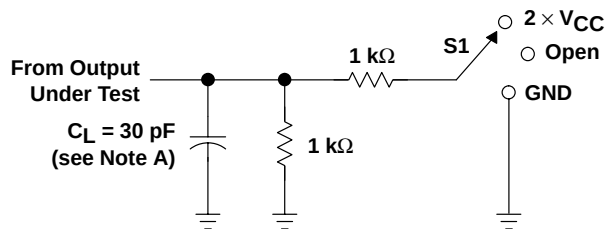
operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER			TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
				TYP	TYP	TYP	
C_{pd}	Power dissipation capacitance per exchanger	All outputs enabled	$C_L = 50\text{ pF}, f = 10\text{ MHz}$	†	87	120	pF
		All outputs disabled		†	80.5	118	

† This information was not available at the time of publication.

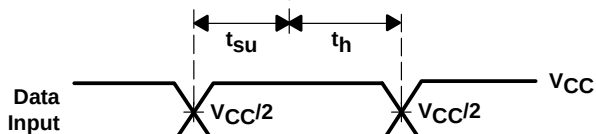
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$

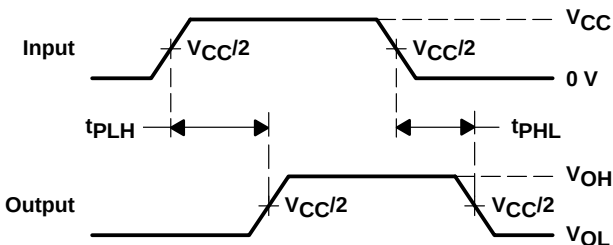


LOAD CIRCUIT

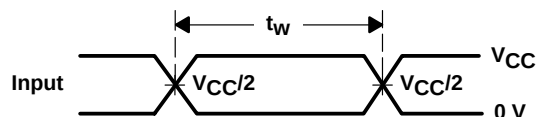
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	$2 \times V_{CC}$
t_{PHZ}/t_{PZH}	GND



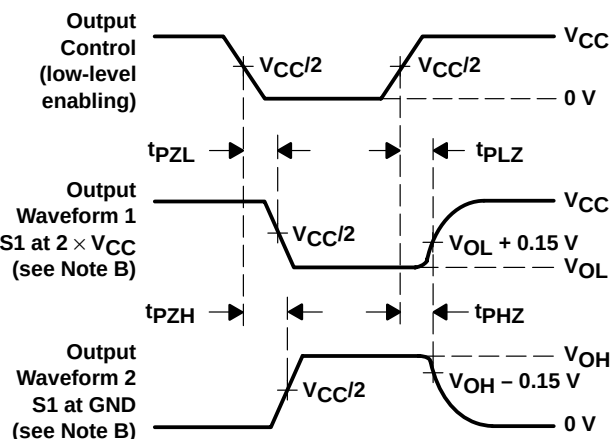
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH16269

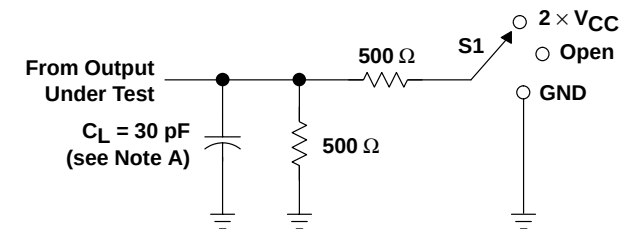
12-BIT TO 24-BIT REGISTERED BUS EXCHANGER

WITH 3-STATE OUTPUTS

SCES019H – JULY 1995 – REVISED FEBRUARY 1999

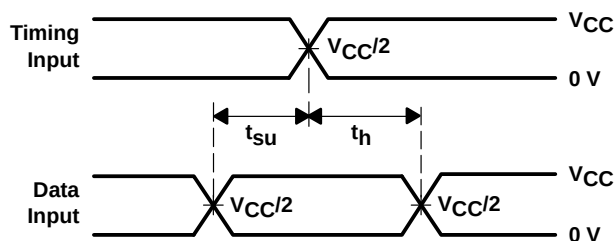
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

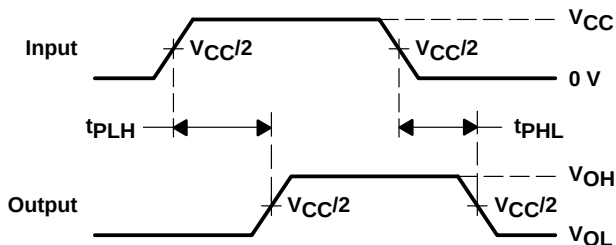


LOAD CIRCUIT

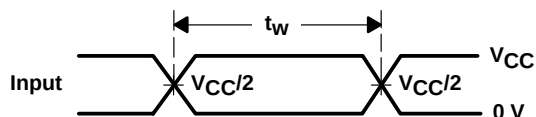
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



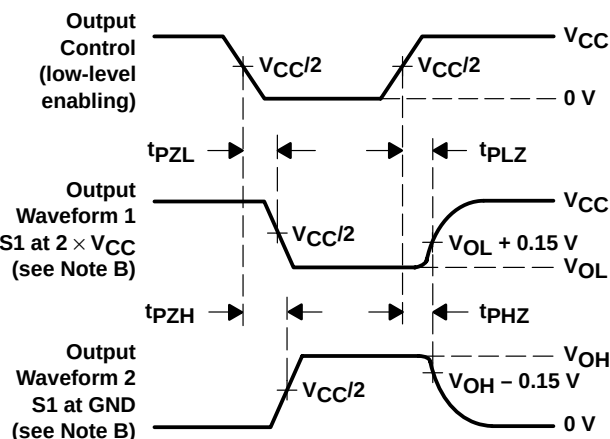
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

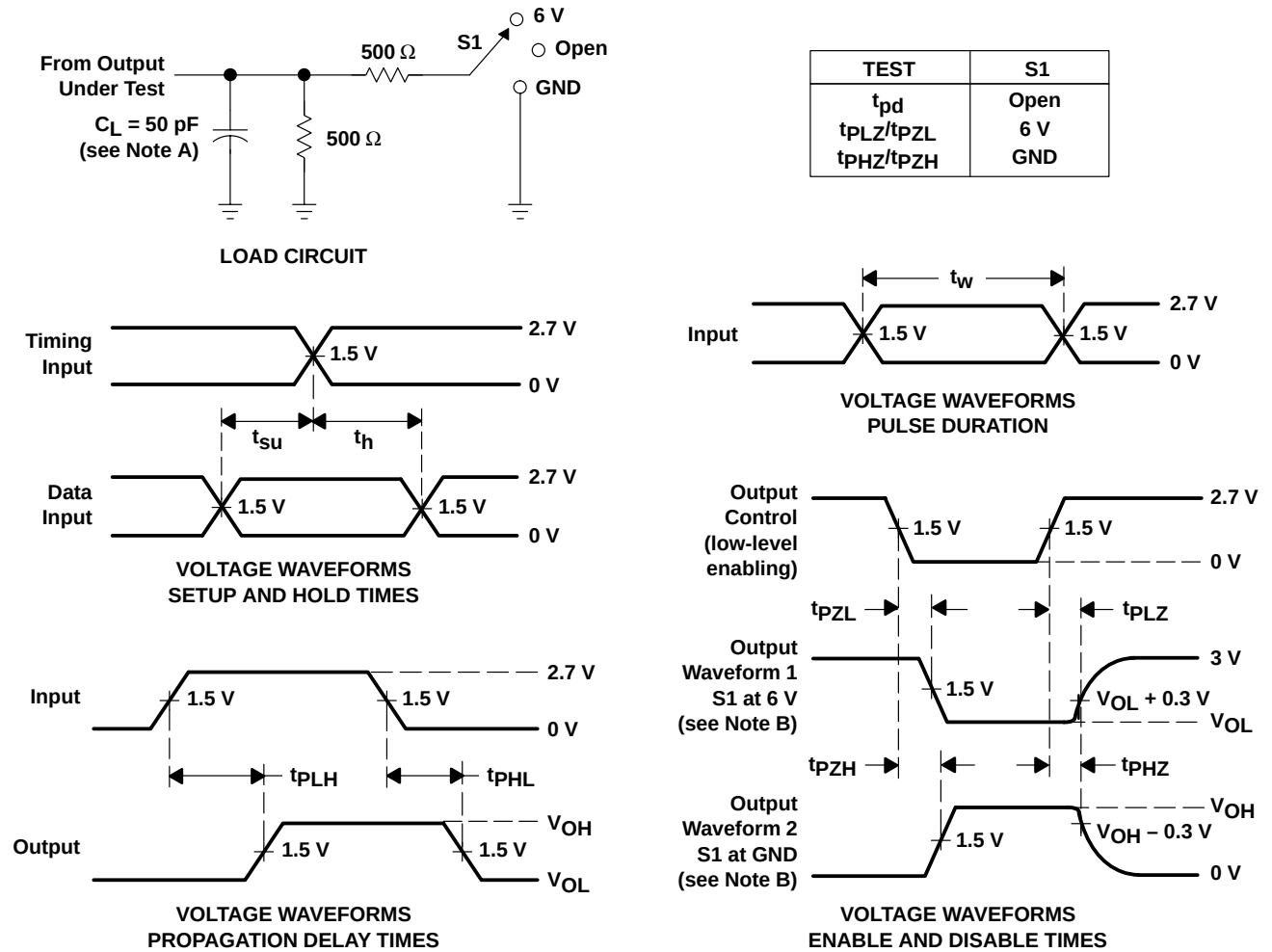
SN74ALVCH16269

12-BIT TO 24-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

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PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16270

12-BIT TO 24-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

SCES028F – JULY 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Package Options Include Plastic Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 12-bit to 24-bit registered bus exchanger is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16270 is used in applications in which data must be transferred from a narrow high-speed bus to a wide lower-frequency bus.

The device provides synchronous data exchange between the two ports. Data is stored in the internal registers on the low-to-high transition of the clock (CLK) input when the appropriate $\overline{CLKEN}$ inputs are low. The select ($\overline{SEL}$) line selects 1B or 2B data for the A outputs. For data transfer in the A-to-B direction, a two-stage pipeline is provided in the A-to-1B path, with a single storage register in the A-to-2B path.

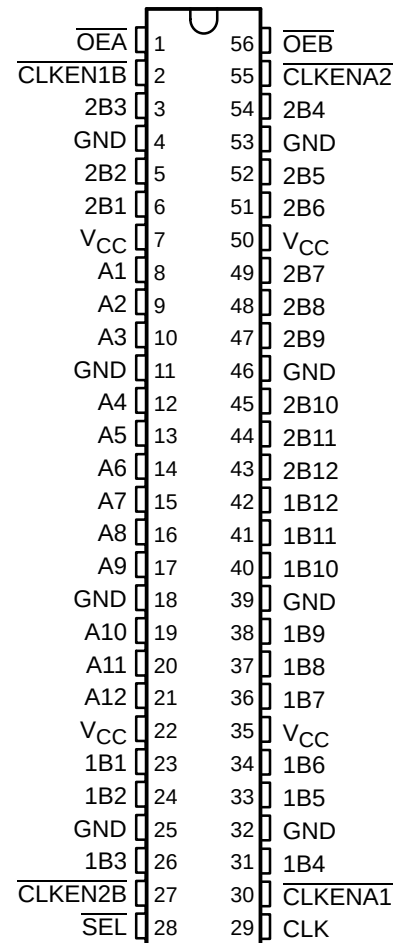
Proper control of the $\overline{CLKENA}$ inputs allows two sequential 12-bit words to be presented synchronously as a 24-bit word on the B port. Data flow is controlled by the active-low output enables ($\overline{OEA}$, $\overline{OEB}$). The control terminals are registered to synchronize the bus-direction changes with CLK.

To ensure the high-impedance state during power up or power down, a clock pulse should be applied as soon as possible and $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver. Due to $\overline{OE}$ being routed through a register, the active state of the outputs cannot be determined prior to the arrival of the first clock pulse.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16270 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)



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SN74ALVCH16270

12-BIT TO 24-BIT REGISTERED BUS EXCHANGER

WITH 3-STATE OUTPUTS

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Function Tables

OUTPUT ENABLE

INPUTS			OUTPUTS	
CLK	$\overline{\text{OEA}}$	$\overline{\text{OEB}}$	A	1B, 2B
↑	H	H	Z	Z
↑	H	L	Z	Active
↑	L	H	Active	Z
↑	L	L	Active	Active

A-TO-B STORAGE ($\overline{\text{OEB}} = \text{L}$)

INPUTS				OUTPUTS	
$\overline{\text{CLKENA1}}$	$\overline{\text{CLKENA2}}$	CLK	A	1B	2B
L	H	X	X	$1\text{B}_0^\dagger$	$2\text{B}_0^\dagger$
L	H	X	X	$1\text{B}_0^\dagger$	$2\text{B}_0^\dagger$
L	L	↑	L	$\text{L}^\ddagger$	L
L	L	↑	H	$\text{H}^\ddagger$	H
H	L	↑	L	$1\text{B}_0^\dagger$	L
H	L	↑	H	$1\text{B}_0^\dagger$	H
H	H	X	X	$1\text{B}_0^\dagger$	$2\text{B}_0^\dagger$

† Output level before the indicated steady-state input conditions were established

‡ Two CLK edges are needed to propagate data.

B-TO-A STORAGE ($\overline{\text{OEA}} = \text{L}$)

INPUTS						OUTPUT A
$\overline{\text{CLKEN1B}}$	$\overline{\text{CLKEN2B}}$	CLK	$\overline{\text{SEL}}$	1B	2B	
H	X	X	H	X	X	$\text{A}_0^\dagger$
X	H	X	L	X	X	$\text{A}_0^\dagger$
L	X	↑	H	L	X	L
L	X	↑	H	H	X	H
X	L	↑	L	X	L	L
X	L	↑	L	X	H	H

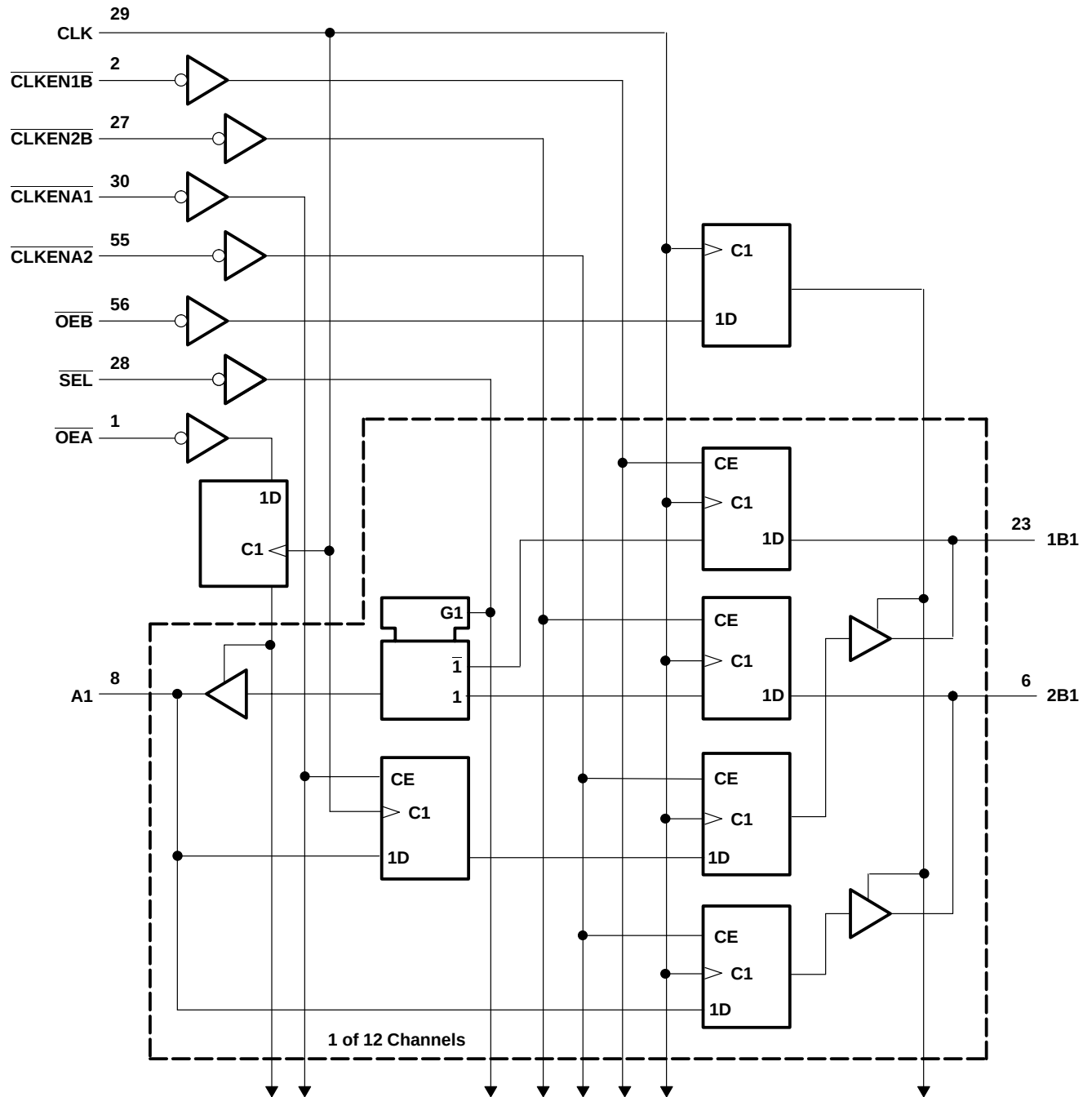
† Output level before the indicated steady-state input conditions were established

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12-BIT TO 24-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

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logic diagram (positive logic)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ} [§]	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3.5		pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V	9		pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.



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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT		
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX			
f _{clock}	Clock frequency	†		150		150		150		MHz		
t _w	Pulse duration, CLK high or low	†		3.3		3.3		3.3		ns		
t _{su}	Setup time	A data before CLK↑		†		4.1		3.8		3.1		ns
		B data before CLK↑		†		0.9		1.2		0.9		
		CLKENA1 or CLKENA2 before CLK↑		†		3.5		3.2		2.7		
		CLKEN1B or CLKEN2B before CLK↑		†		3.4		3		2.6		
		OE data before CLK↑		†		4.4		3.9		3.2		
t _h	Hold time	A data after CLK↑		†		0		0		0.2		ns
		B data after CLK↑		†		1.4		1		1.7		
		CLKENA1 or CLKENA2 after CLK↑		†		0		0.1		0.3		
		CLKEN1B or CLKEN2B after CLK↑		†		0		0		0.6		
		OE after CLK↑		†		0		0		0.1		

† This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 1.8\text{ V}$		$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f_{max}			†		150		150		150		MHz
t_{pd}	CLK	B	†		1.5	5.9	5.8		1.1	5.1	ns
		A	†		1.2	5.4	5.4		1	4.7	
	$\overline{SEL}$	A	†		1.4	6.2	6.4		1	5.5	
t_{en}	CLK	A or B	†		1.5	7	6.8		1	6	ns
t_{dis}	CLK	A or B	†		1.9	7.2	6.5		1.1	5.8	ns

† This information was not available at the time of publication.

operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd}	Power dissipation capacitance	Outputs enabled	†	87	120	pF
		Outputs disabled	†	80.5	118	

† This information was not available at the time of publication.



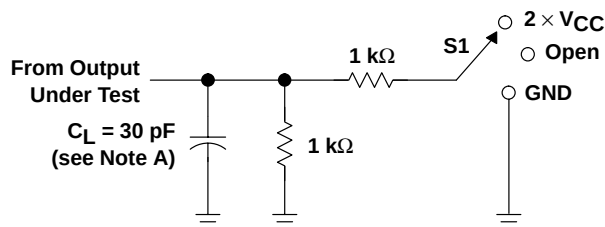
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12-BIT TO 24-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

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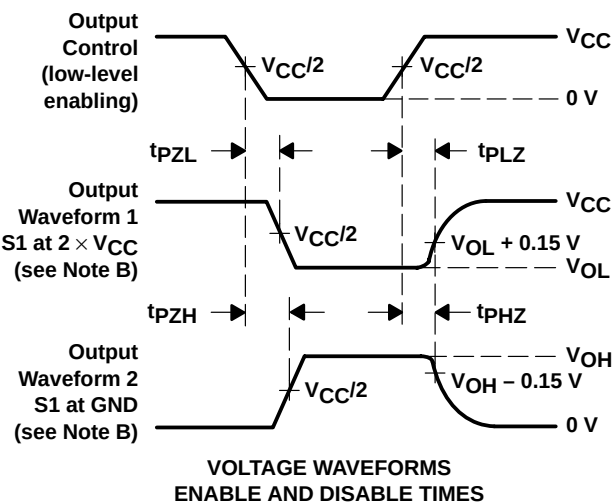
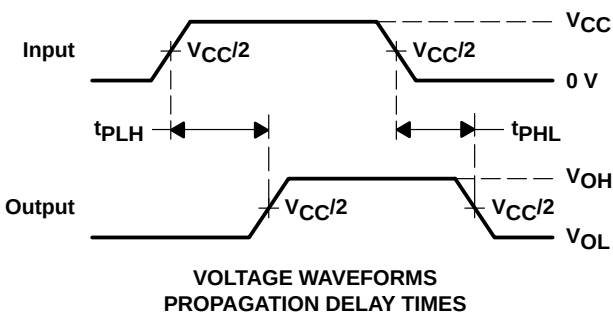
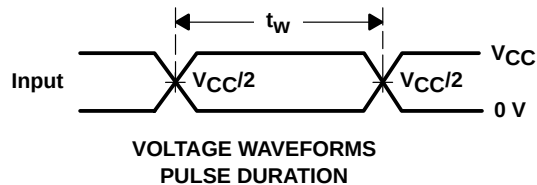
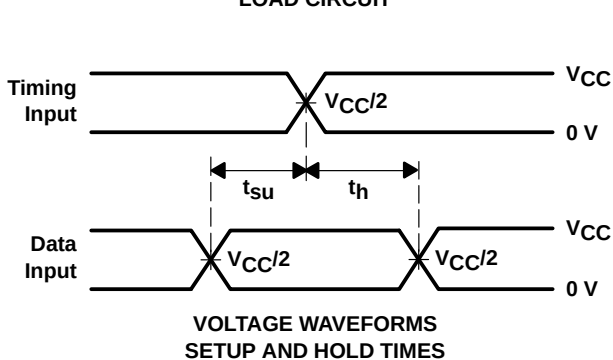
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: PRR $\leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

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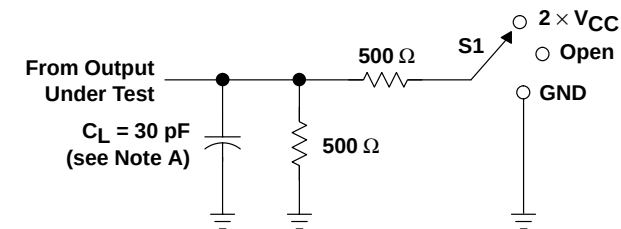
12-BIT TO 24-BIT REGISTERED BUS EXCHANGER

WITH 3-STATE OUTPUTS

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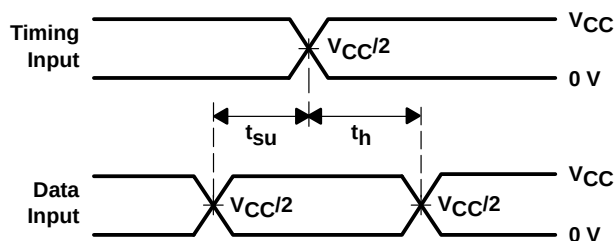
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

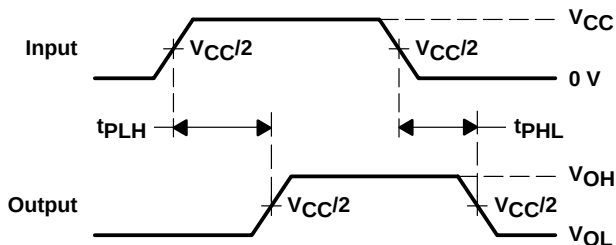


LOAD CIRCUIT

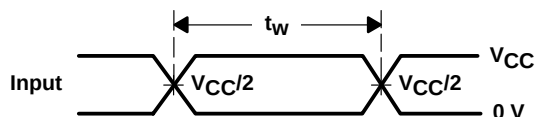
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



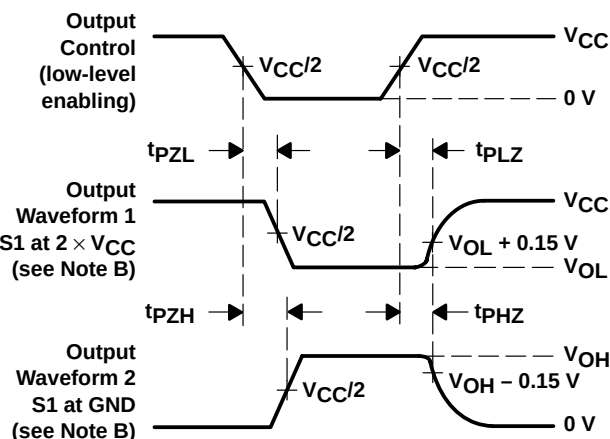
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

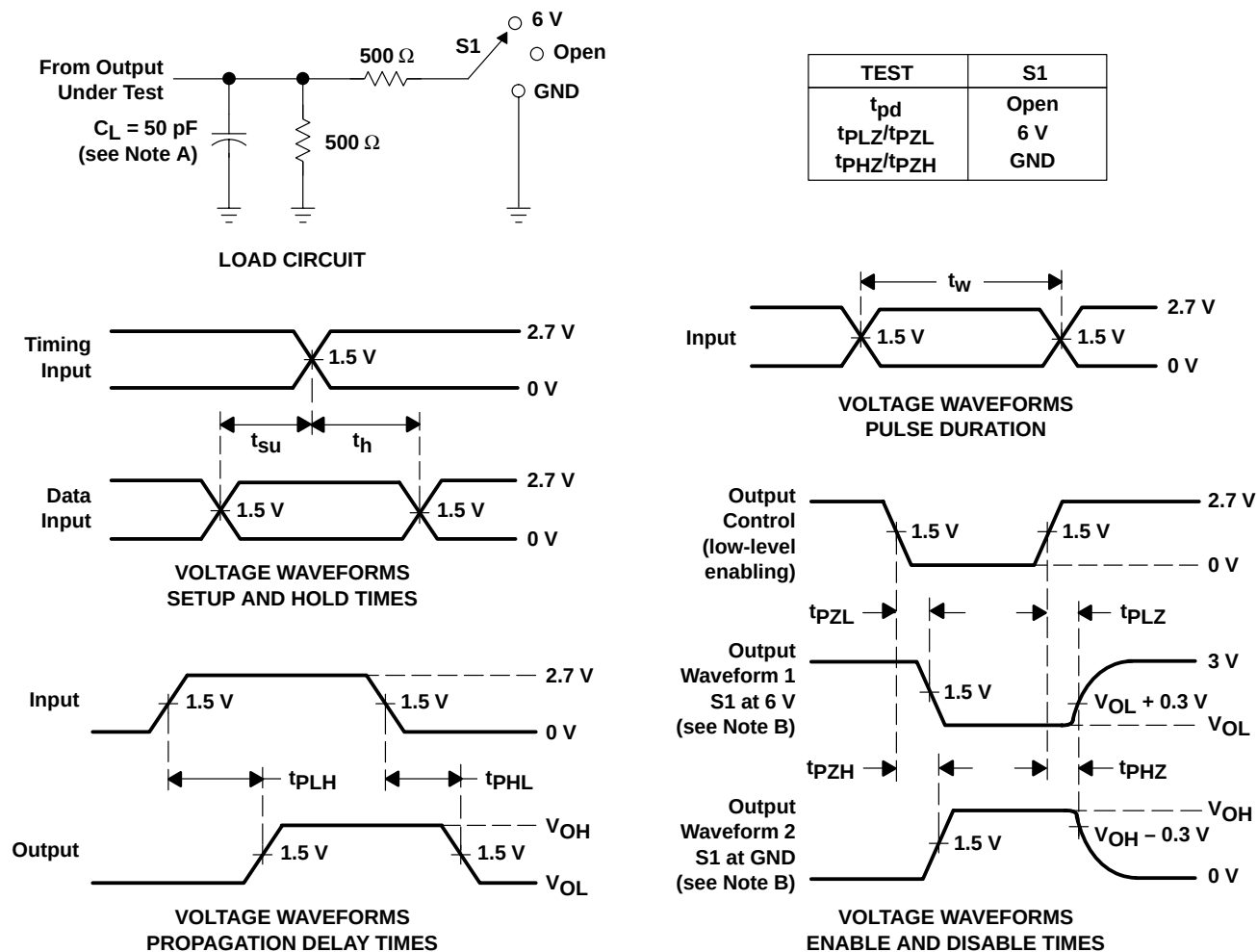
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12-BIT TO 24-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

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PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

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12-BIT TO 24-BIT MULTIPLEXED BUS EXCHANGER WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 12-bit to 24-bit bus exchanger is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16271 is intended for applications in which two separate data paths must be multiplexed onto, or demultiplexed from, a single data path. This device is particularly suitable as an interface between conventional DRAMs and high-speed microprocessors.

A data is stored in the internal A-to-B registers on the low-to-high transition of the clock (CLK) input, provided that the clock-enable ($\overline{CLKENA}$) inputs are low. Proper control of these inputs allows two sequential 12-bit words to be presented as a 24-bit word on the B port.

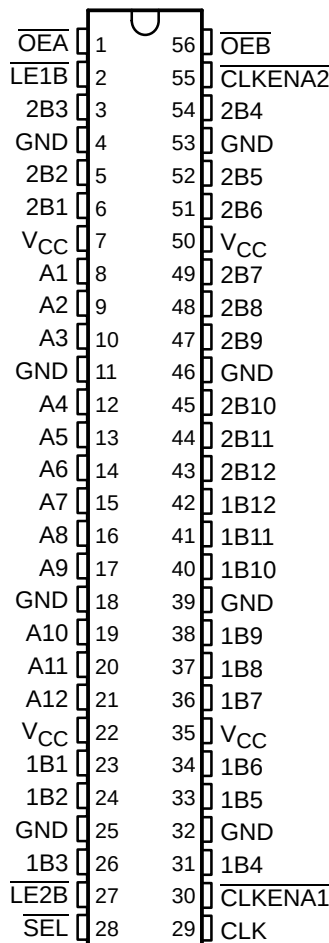
Transparent latches in the B-to-A path allow asynchronous operation to maximize memory access throughput. These latches transfer data when the latch-enable ($\overline{LE}$) inputs are low. The select ($\overline{SEL}$) line selects 1B or 2B data for the A outputs. Data flow is controlled by the active-low output enables ($\overline{OEA}$, $\overline{OEB}$).

To ensure the high-impedance state during power up or power down, the output enables should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16271 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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12-BIT TO 24-BIT MULTIPLEXED BUS EXCHANGER
WITH 3-STATE OUTPUTS

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Function Tables

OUTPUT ENABLE

INPUTS		OUTPUTS	
$\overline{\text{OEA}}$	$\overline{\text{OEB}}$	A	1B, 2B
H	H	Z	Z
H	L	Z	Active
L	H	Active	Z
L	L	Active	Active

A-TO-B STORAGE ($\overline{\text{OEB}} = \text{L}$)

INPUTS				OUTPUTS	
$\overline{\text{CLKENA1}}$	$\overline{\text{CLKENA2}}$	CLK	A	1B	2B
H	H	X	X	$1\text{B}_0^\dagger$	$2\text{B}_0^\dagger$
L	X	$\uparrow$	L	L	X
L	X	$\uparrow$	H	H	X
X	L	$\uparrow$	L	X	L
X	L	$\uparrow$	H	A_0	H

B-TO-A STORAGE ($\overline{\text{OEA}} = \text{L}$)

INPUTS				OUTPUT A
$\overline{\text{LE}}$	$\overline{\text{SEL}}$	1B	2B	
H	X	X	X	$\text{A}_0^\dagger$
H	X	X	X	$\text{A}_0^\dagger$
L	H	L	X	L
L	H	H	X	H
L	L	X	L	L
L	L	X	H	H

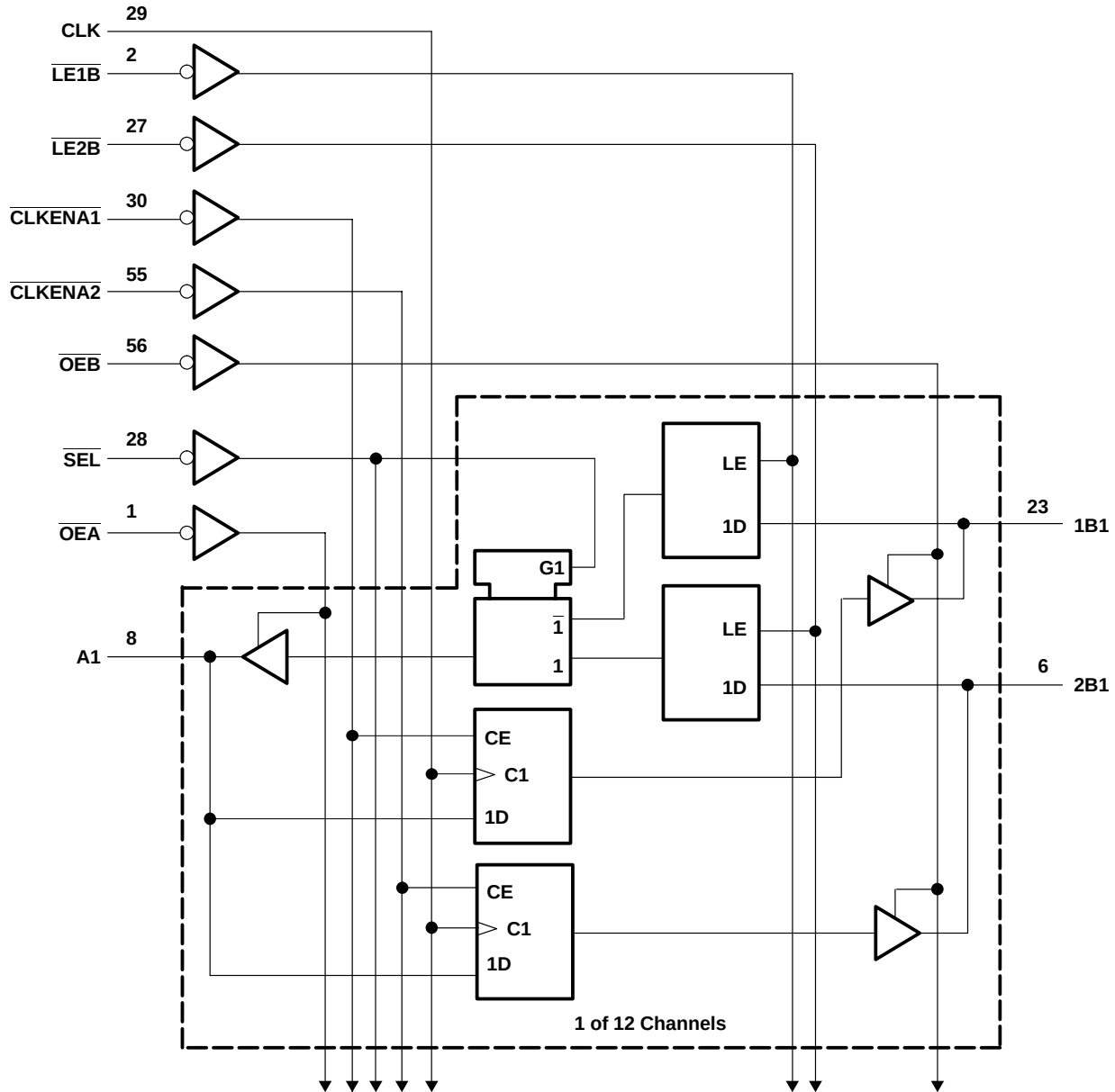
† Output level before the indicated steady-state input conditions were established

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logic diagram (positive logic)



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12-BIT TO 24-BIT MULTIPLEXED BUS EXCHANGER

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 μA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA		2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 μA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA		2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V	±5			μA
I _I (hold)		V _I = 0.58 V	1.65 V	25			μA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ} [§]		V _O = V _{CC} or GND	3.6 V	±10			μA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			μA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			μA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3.5			pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V	9			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency		¶		130		130		130		MHz
t _w	Pulse duration, CLK high or low		¶		3.3		3.3		3.3		ns
t _{su}	Setup time	A before CLK↑	¶		2.6		2.1		1.7		ns
		B before $\overline{\text{LE}}$	¶		1.7		1.5		1.3		
		$\overline{\text{CLKEN}}$ before CLK↑	¶		1.6		1.3		1		
t _h	Hold time	A after CLK↑	¶		0.6		0.6		0.7		ns
		B after $\overline{\text{LE}}$	¶		0.9		0.9		1.1		
		$\overline{\text{CLKEN}}$ after CLK↑	¶		1		0.9		0.9		

¶ This information was not available at the time of publication.



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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		130		130		130		MHz
t _{pd}	CLK	B		†	1	6.2		5	1	4.3	ns
	B	A		†	1	5.3		4.7	1.4	4	
	$\overline{\text{LE}}$			†	1	6		5.9	1.4	4.8	
	$\overline{\text{SEL}}$			†	1.1	6.4		6.2	1.3	5.2	
t _{en}	$\overline{\text{OEB}}$ or $\overline{\text{OEA}}$	B or A		†	1	6		6.1	1	5.1	ns
t _{dis}	$\overline{\text{OEB}}$ or $\overline{\text{OEA}}$	B or A		†	1.4	5.4		4.6	1.7	4.2	ns

† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd} Power dissipation capacitance	A to B	Outputs enabled	C _L = 0, f = 10 MHz	†	92	105	pF
		Outputs disabled		†	61	76	
	B to A	Outputs enabled		†	39	43	
		Outputs disabled		†	11	13	

† This information was not available at the time of publication.

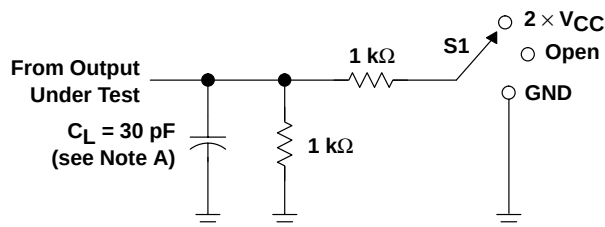
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12-BIT TO 24-BIT MULTIPLEXED BUS EXCHANGER WITH 3-STATE OUTPUTS

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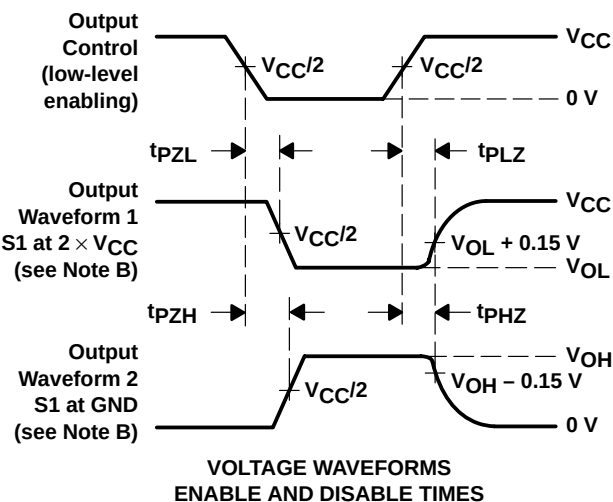
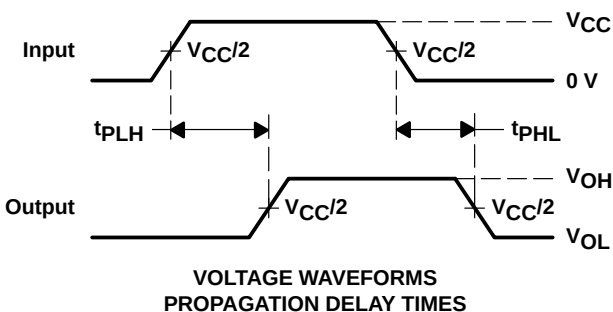
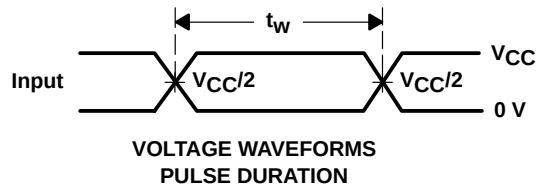
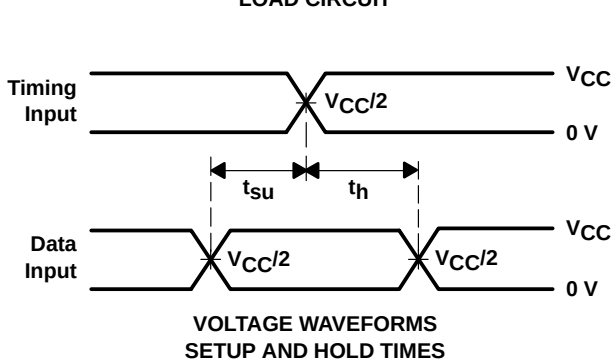
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

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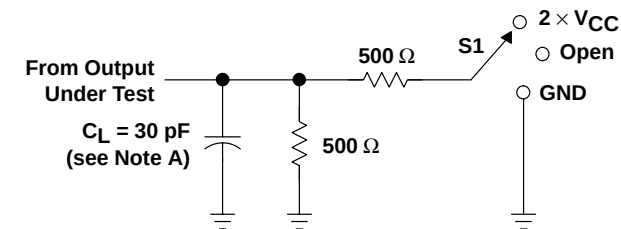
12-BIT TO 24-BIT MULTIPLEXED BUS EXCHANGER

WITH 3-STATE OUTPUTS

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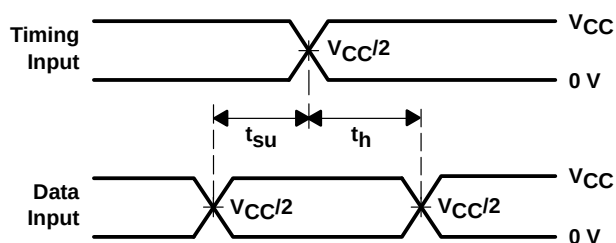
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

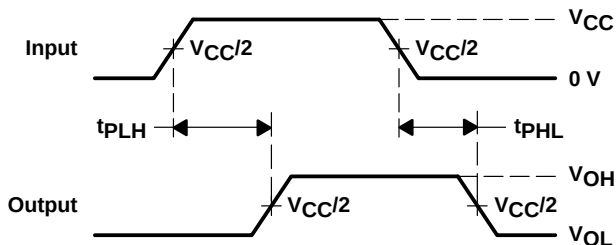


LOAD CIRCUIT

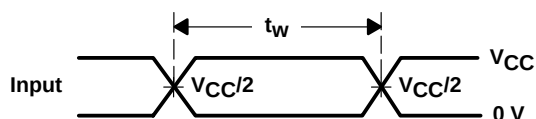
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



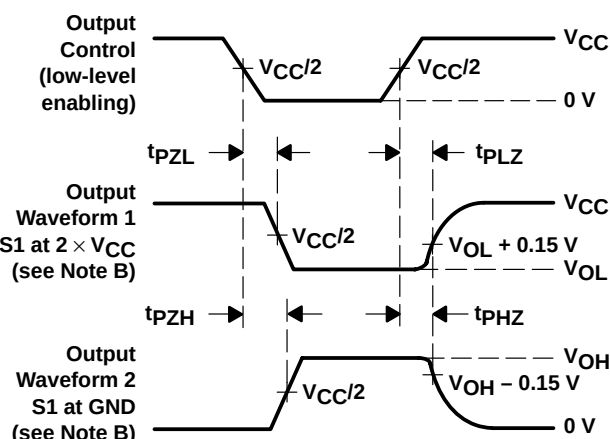
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

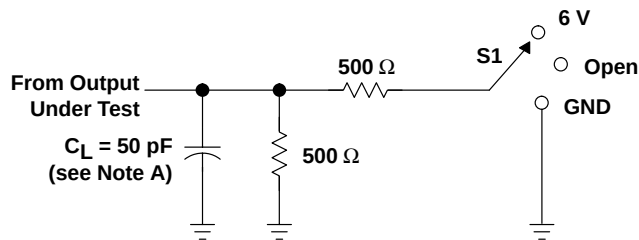
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12-BIT TO 24-BIT MULTIPLEXED BUS EXCHANGER WITH 3-STATE OUTPUTS

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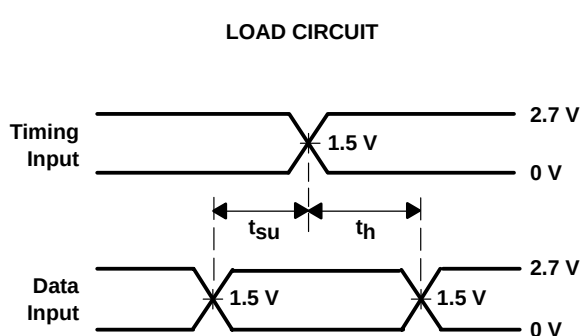
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

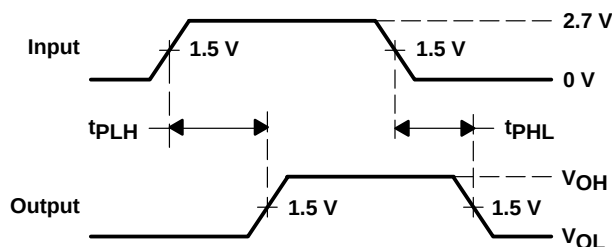


LOAD CIRCUIT

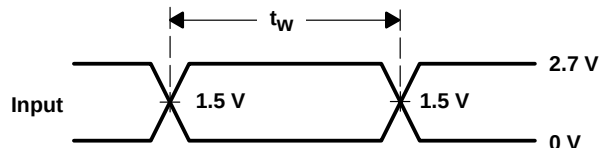
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PHL}	GND



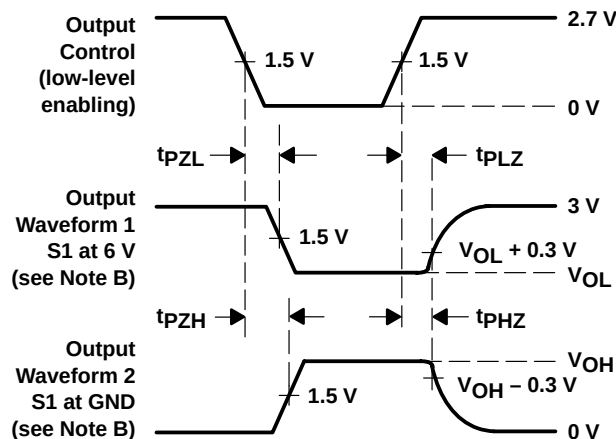
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16272 12-BIT TO 24-BIT MULTIPLEXED BUS EXCHANGER WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Packaged in Plastic Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 12-bit to 24-bit bus exchanger is designed for 1.65-V to 3.3-V V_{CC} operation.

The SN74ALVCH16272 is intended for applications where two separate datapaths must be multiplexed onto, or demultiplexed from, a single datapath. This device is particularly suitable as an interface between conventional DRAMs and high-speed microprocessors.

Data from the A inputs is stored in the internal registers on the low-to-high transition of the clock (CLK) input, when the $\overline{CLKENA}$ inputs are low. A two-stage pipeline is provided in each of the A-to-1B and A-to-2B paths to serve as a shallow write buffer.

Transparent latches are provided in the B-to-A path to allow asynchronous operation to maximize memory access throughput. These latches transfer data when the latch-enable ($\overline{LE}$) inputs are low. The select ($\overline{SEL}$) line selects 1B or 2B data for the A outputs. Data flow is controlled by the active-low output enables ($\overline{OEA}$, $\overline{OEB}$).

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16272 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)

$\overline{OEA}$	1	56	$\overline{OEB}$
$\overline{LE1B}$	2	55	$\overline{CLKENA2}$
2B3	3	54	2B4
GND	4	53	GND
2B2	5	52	2B5
2B1	6	51	2B6
V_{CC}	7	50	V_{CC}
A1	8	49	2B7
A2	9	48	2B8
A3	10	47	2B9
GND	11	46	GND
A4	12	45	2B10
A5	13	44	2B11
A6	14	43	2B12
A7	15	42	1B12
A8	16	41	1B11
A9	17	40	1B10
GND	18	39	GND
A10	19	38	1B9
A11	20	37	1B8
A12	21	36	1B7
V_{CC}	22	35	V_{CC}
1B1	23	34	1B6
1B2	24	33	1B5
GND	25	32	GND
1B3	26	31	1B4
$\overline{LE2B}$	27	30	$\overline{CLKENA1}$
$\overline{SEL}$	28	29	CLK

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SN74ALVCH16272
12-BIT TO 24-BIT MULTIPLEXED BUS EXCHANGER
WITH 3-STATE OUTPUTS

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Function Tables

OUTPUT ENABLE

INPUTS		OUTPUTS	
$\overline{\text{OEA}}$	$\overline{\text{OEB}}$	A	1B, 2B
H	H	Z	Z
H	L	Z	Active
L	H	Active	Z
L	L	Active	Active

A-TO-B STORAGE
($\overline{\text{OEB}} = \text{L}$)

INPUTS				OUTPUTS	
$\overline{\text{CLKENA1}}$	$\overline{\text{CLKENA2}}$	CLK	A	1B	2B
H	H	X	X	1B ₀ [†]	2B ₀ [†]
L	X	↑	L	L [‡]	X
L	X	↑	H	H [‡]	X
X	L	↑	L	X	L
X	L	↑	H	A ₀	H

† Output level before the indicated steady-state input conditions were established

‡ Two CLK edges are needed to propagate data.

B-TO-A STORAGE
($\overline{\text{OEA}} = \text{L}$)

INPUTS				OUTPUT A
$\overline{\text{LE}}$	$\overline{\text{SEL}}$	1B	2B	
H	X	X	X	A ₀ [†]
H	X	X	X	A ₀ [†]
L	H	L	X	L
L	H	H	X	H
L	L	X	L	L
L	L	X	H	H

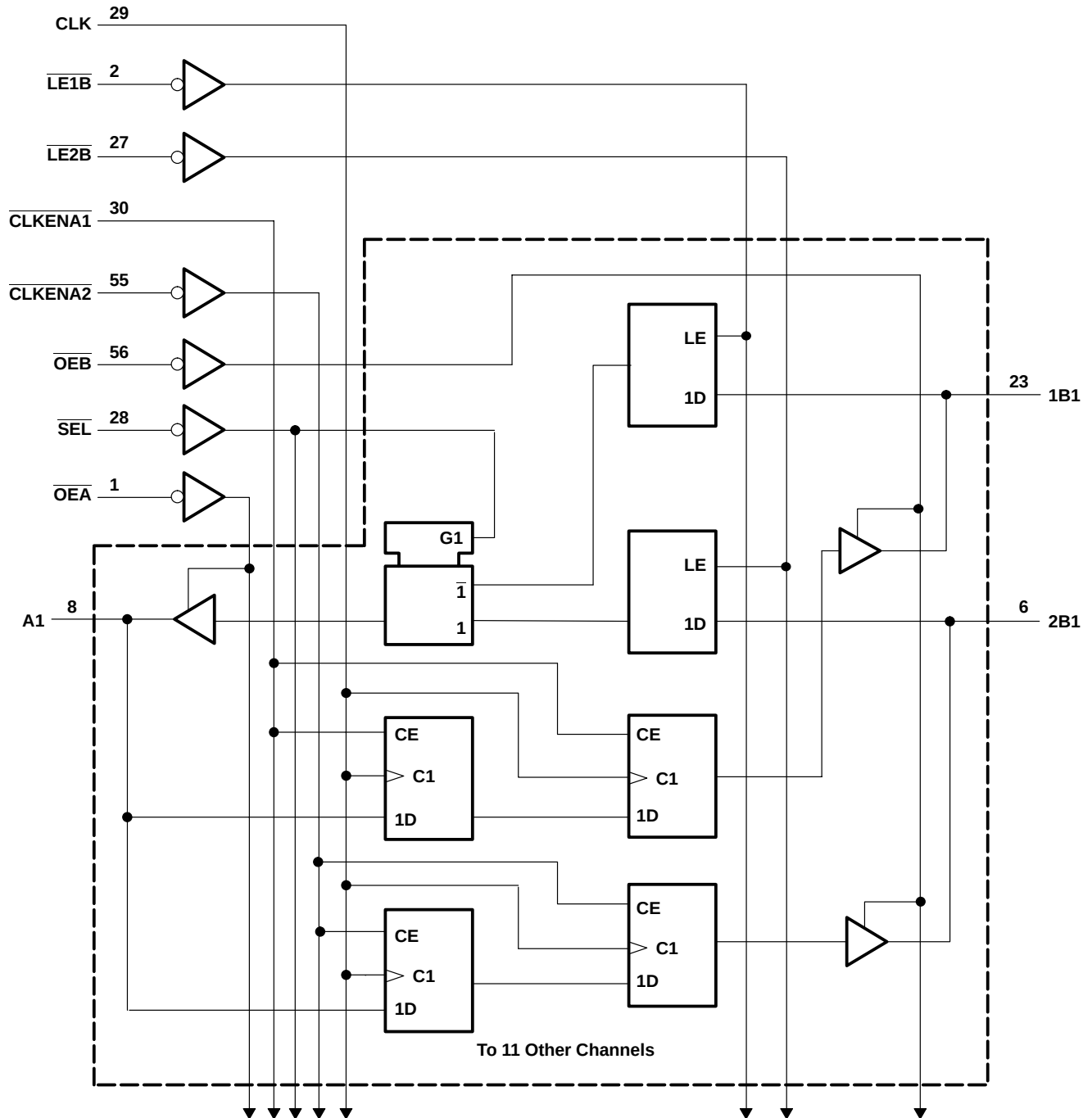
† Output level before the indicated steady-state input conditions were established

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logic diagram (positive logic)



PRODUCT PREVIEW

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ} [§]	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V			pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency									MHz
t _w	Pulse duration, CLK high or low									ns
t _{su}	Setup time	A before CLK↑								ns
		B before $\overline{\text{LE}}$								
		$\overline{\text{CLKEN}}$ before CLK↑								
t _h	Hold time	A after CLK↑								ns
		B after $\overline{\text{LE}}$								
		$\overline{\text{CLKEN}}$ after CLK↑								



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WITH 3-STATE OUTPUTS

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}											MHz
t _{pd}	CLK	B									ns
	B	A									
	$\overline{\text{LE}}$										
	$\overline{\text{SEL}}$										
t _{en}	$\overline{\text{OEB}}$ or $\overline{\text{OEA}}$	B or A									ns
t _{dis}	$\overline{\text{OEB}}$ or $\overline{\text{OEA}}$	B or A									ns

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd} Power dissipation capacitance	A to B	Outputs enabled	C _L = 0, f = 10 MHz				pF
		Outputs disabled					
	B to A	Outputs enabled					
		Outputs disabled					

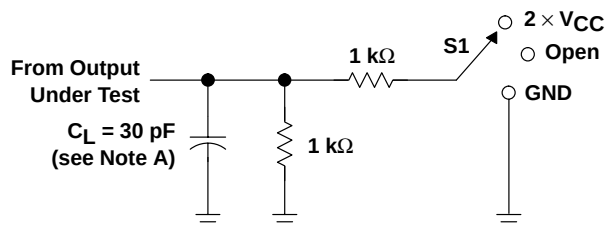
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12-BIT TO 24-BIT MULTIPLEXED BUS EXCHANGER WITH 3-STATE OUTPUTS

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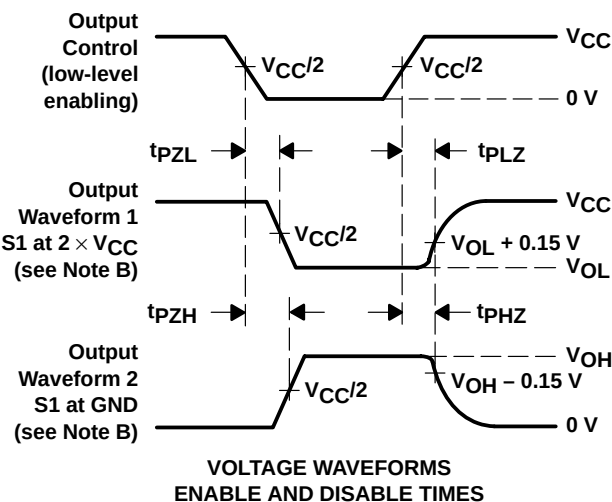
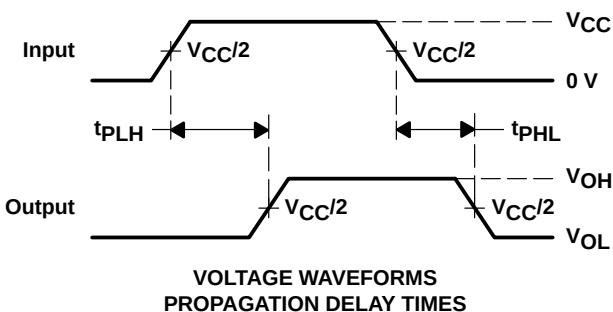
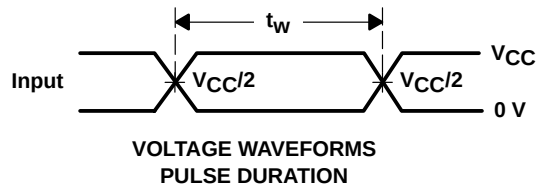
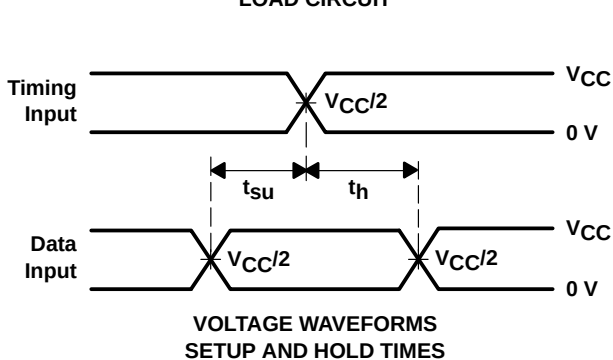
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

PRODUCT PREVIEW

SN74ALVCH16272

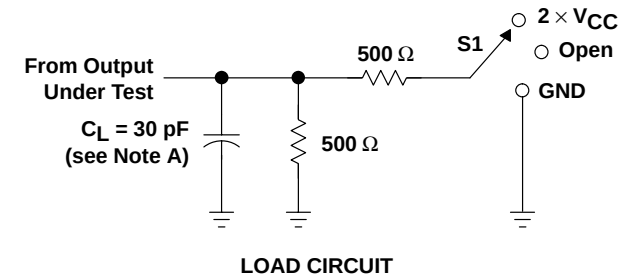
12-BIT TO 24-BIT MULTIPLEXED BUS EXCHANGER

WITH 3-STATE OUTPUTS

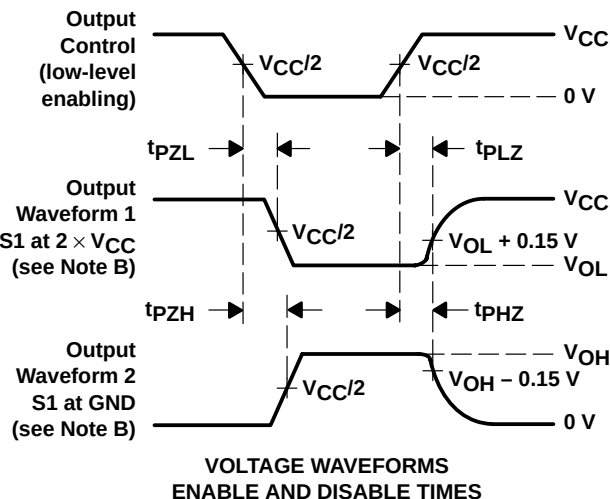
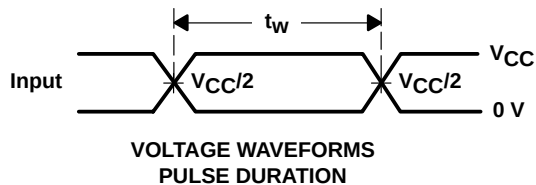
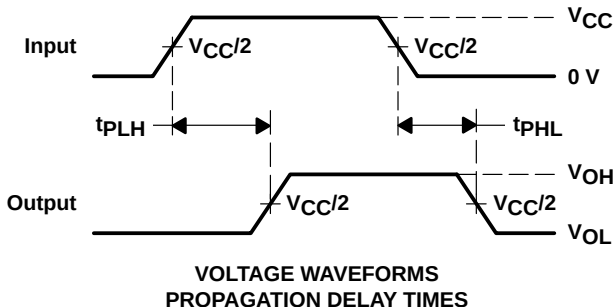
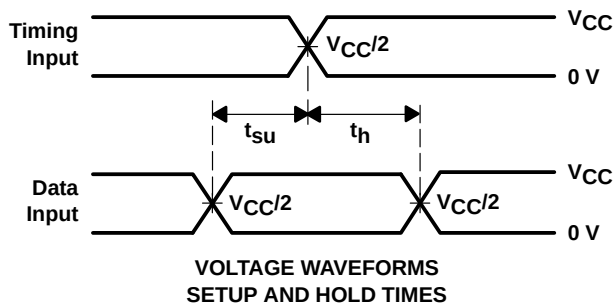
SCES057C – OCTOBER 1995 – REVISED FEBRUARY 1999

PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$



TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

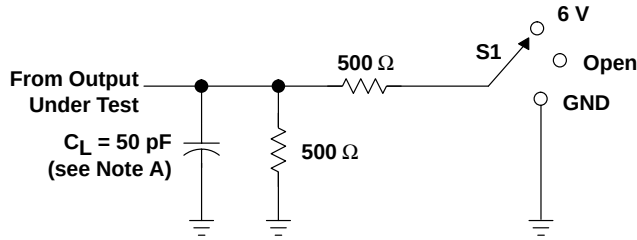
SN74ALVCH16272

12-BIT TO 24-BIT MULTIPLEXED BUS EXCHANGER WITH 3-STATE OUTPUTS

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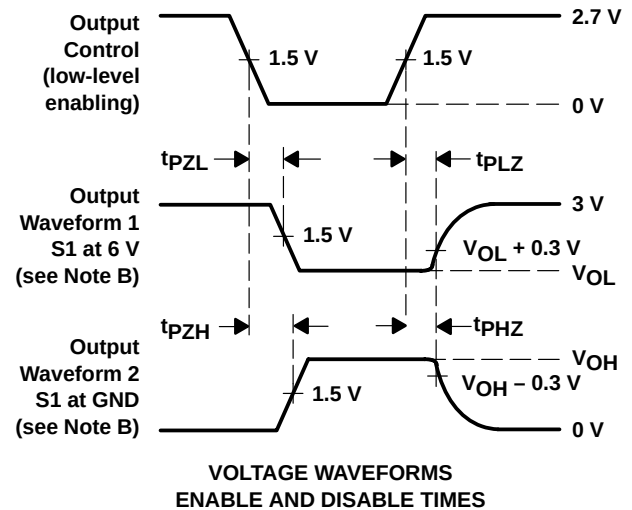
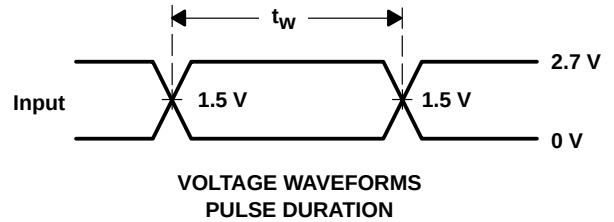
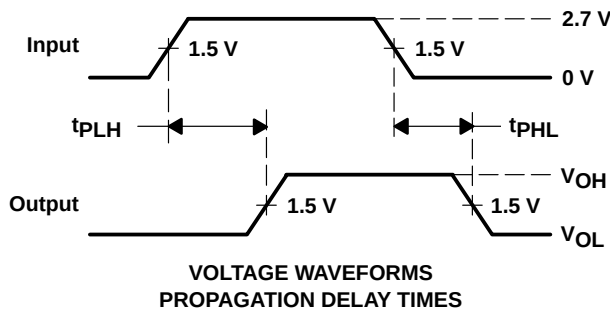
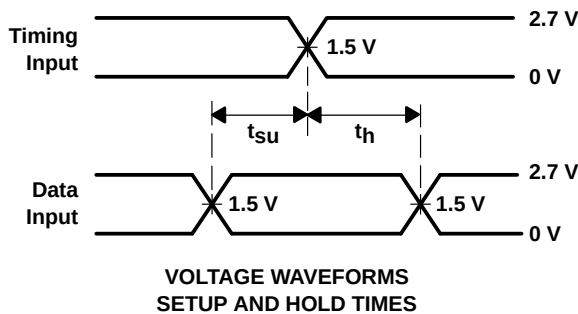
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PHL}	GND



- NOTES: A. C_L includes probe and jig capacitance.
 B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 D. The outputs are measured one at a time with one transition per measurement.
 E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 F. t_{PZL} and t_{PZH} are the same as t_{en} .
 G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveform

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SN74ALVCH16280

16-BIT TO 32-BIT REGISTERED BUS EXCHANGER WITH BYTE MASKS AND 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Packaged in Thin Shrink Small-Outline Package

description

This 16-bit to 32-bit registered bus exchanger is designed for 1.65-V to 3.6-V V_{CC} operation. This device is intended for use in applications where data must be transferred from a narrow high-speed bus to a wide lower-frequency bus.

The device provides synchronous data exchange between the A and B ports. Data is stored in the internal registers on the low-to-high transition of the clock (CLK) input. For data transfer in the B-to-A direction, $\overline{SEL}$ selects 1B or 2B data for the A outputs.

For data transfer in the A-to-B direction, a two-stage pipeline is provided in the 1B path, and a single storage register in the 2B path. Data flow is controlled by the active-low output enable ($\overline{OE}$) and the direction-control (DIR) input. DIR is registered to synchronize the bus direction changes with the clock.

Two mask bits are provided for both data bytes. The D outputs are controlled by the active-low $\overline{OE}$.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16280 is characterized for operation from -40°C to 85°C .

DBB PACKAGE
(TOP VIEW)

V_{CC}	1	80	V_{CC}
GND	2	79	GND
2B7	3	78	1B8
1B7	4	77	2B8
2B6	5	76	1B9
GND	6	75	GND
1B6	7	74	2B9
2B5	8	73	1B10
1B5	9	72	2B10
V_{CC}	10	71	V_{CC}
2B4	11	70	1B11
1B4	12	69	2B11
2B3	13	68	1B12
1B3	14	67	2B12
GND	15	66	GND
2B2	16	65	1B13
1B2	17	64	2B13
2B1	18	63	1B14
1B1	19	62	2B14
V_{CC}	20	61	V_{CC}
GND	21	60	GND
2D2	22	59	1B15
1D2	23	58	2B15
2D1	24	57	1B16
1D1	25	56	2B16
V_{CC}	26	55	V_{CC}
C1	27	54	A16
C2	28	53	A15
A1	29	52	A14
GND	30	51	GND
A2	31	50	A13
A3	32	49	A12
A4	33	48	A11
V_{CC}	34	47	V_{CC}
A5	35	46	A10
A6	36	45	A9
A7	37	44	A8
GND	38	43	GND
CLK	39	42	$\overline{OE}$
$\overline{SEL}$	40	41	DIR

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SN74ALVCH16280

16-BIT TO 32-BIT REGISTERED BUS EXCHANGER WITH BYTE MASKS AND 3-STATE OUTPUTS

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Function Tables

OUTPUT ENABLE

INPUTS			OUTPUTS		
CLK	$\overline{OE}$	DIR	A	1B, 2B	1D, 2D
↑	H	X	Z	Z	Z
↑	L	H	Z	Active	Active
↑	L	L	Active	Z	Active

A-TO-B STORAGE ($\overline{OE} = L$, DIR = H)

INPUTS			OUTPUTS	
SEL	CLK	A	1B	2B
H	X	X	1B ₀ [†]	2B ₀ [†]
L	↑	L	L [‡]	L
L	↑	H	H [‡]	H

[†] Output level before the indicated steady-state input conditions were established

[‡] Two CLK edges are needed to propagate the data.

B-TO-A STORAGE ($\overline{OE} = L$, DIR = L)

INPUTS				OUTPUT
CLK	SEL	1B	2B	A
↑	H	X	L	L [§]
↑	H	X	H	H [§]
↑	L	L	X	L
↑	L	H	X	H

[§] Two clock edges are needed to propagate the data. The data is loaded in the first register when SEL is low and propagates to the second register when SEL is high.

C-TO-D STORAGE ($\overline{OE} = L$)

INPUTS			OUTPUTS	
SEL	CLK	A	1B	2B
H	X	X	1D ₀ [†]	2D ₀ [†]
L	↑	L	L [‡]	L
L	↑	H	H [‡]	H

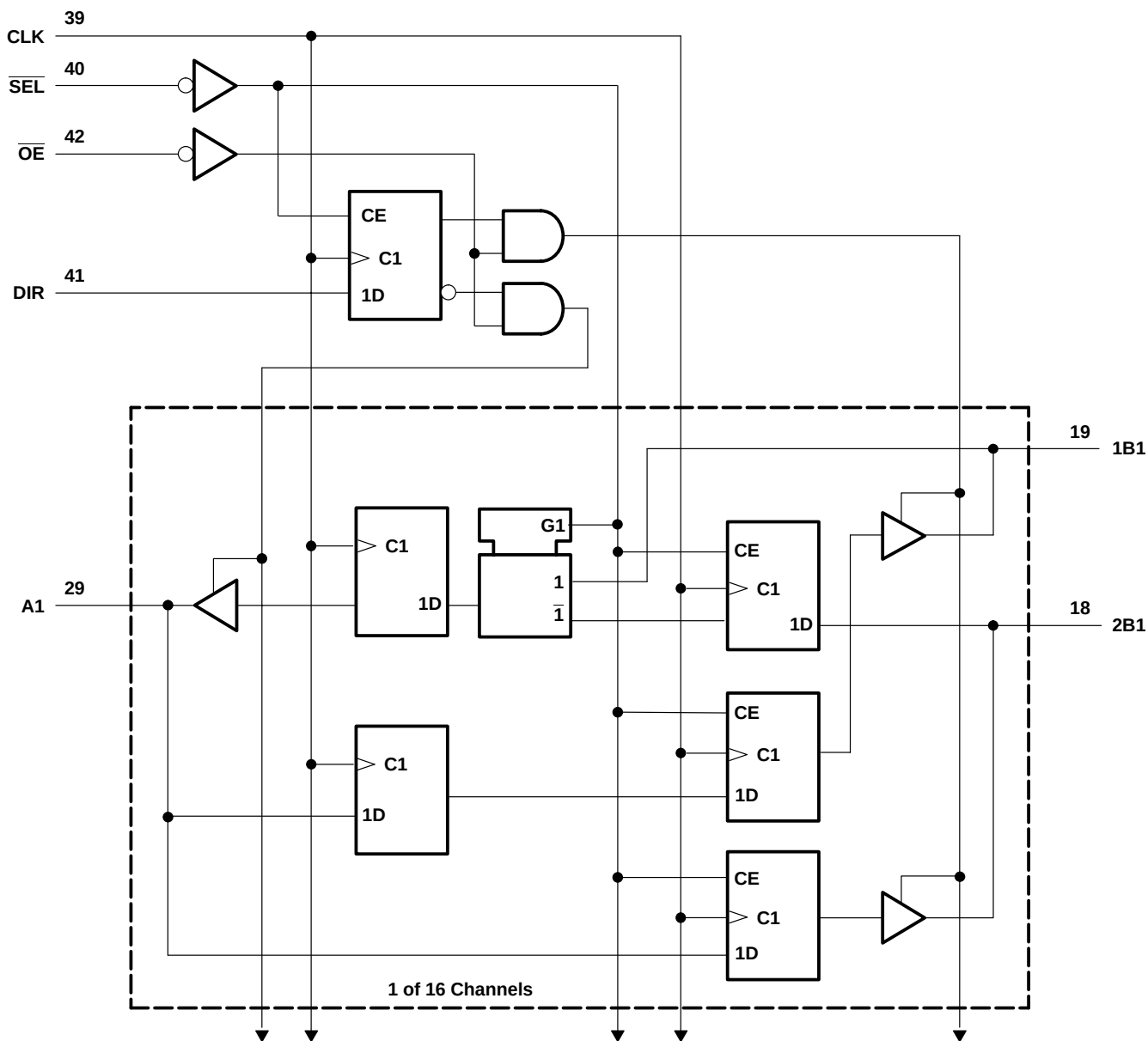
[†] Output level before the indicated steady-state input conditions were established

[‡] Two CLK edges are needed to propagate the data.

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16-BIT TO 32-BIT REGISTERED BUS EXCHANGER
WITH BYTE MASKS AND 3-STATE OUTPUTS

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logic diagram (positive logic)



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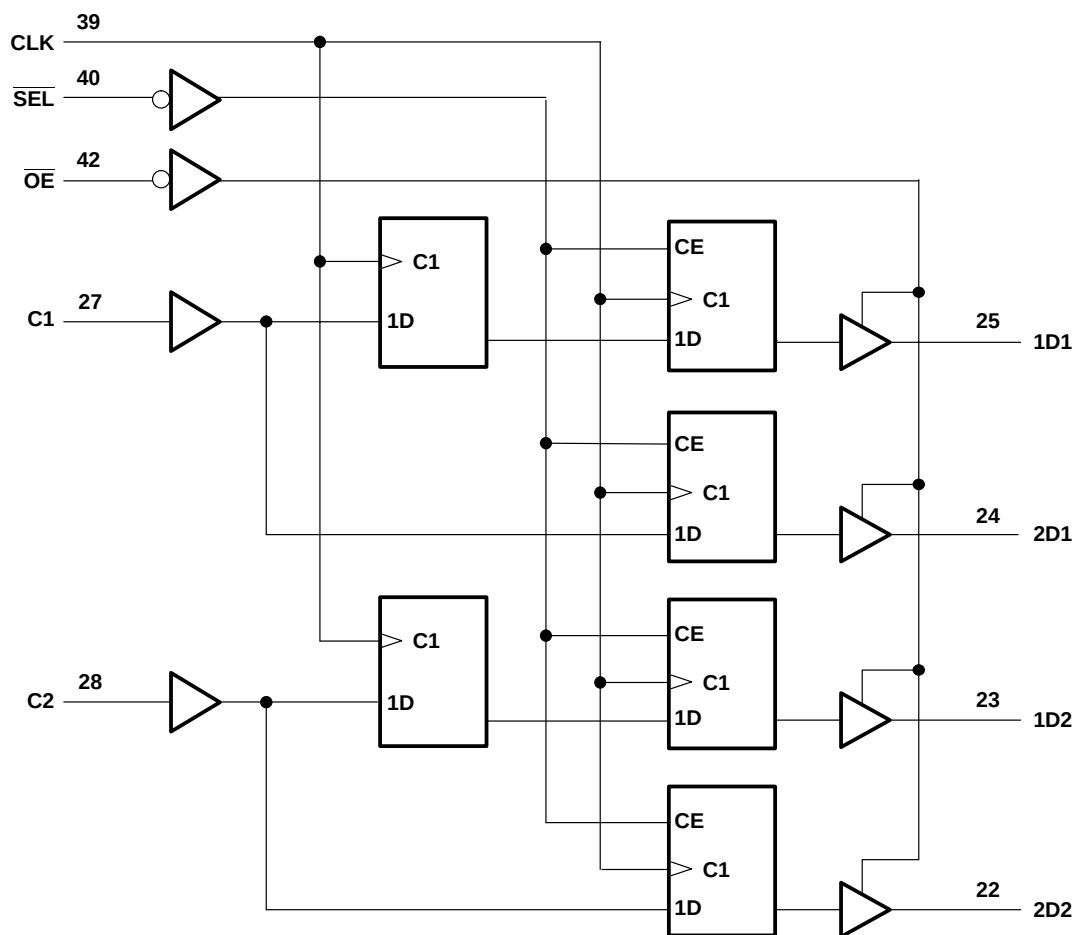


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16-BIT TO 32-BIT REGISTERED BUS EXCHANGER WITH BYTE MASKS AND 3-STATE OUTPUTS

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logic diagram (positive logic) (mask bits)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3)	106°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate		10		ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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16-BIT TO 32-BIT REGISTERED BUS EXCHANGER
WITH BYTE MASKS AND 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ} [§]	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V			pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.

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16-BIT TO 32-BIT REGISTERED BUS EXCHANGER
WITH BYTE MASKS AND 3-STATE OUTPUTS

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT	
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
f _{clock}	Clock frequency										MHz
t _w	Pulse duration, CLK high or low										ns
t _{su}	Setup time	A data before CLK↑									ns
		B data before CLK↑									
		DIR before CLK↑									
		$\overline{\text{SEL}}$ before CLK↑									
t _h	Hold time	A data after CLK↑									ns
		B data after CLK↑									
		DIR after CLK↑									
		$\overline{\text{SEL}}$ after CLK↑									

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 1.8\text{ V}$		$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f_{max}											MHz
t_{pd}	CLK	A									ns
		B									
t_{en}	$\overline{\text{OE}}$	A									ns
		B									
t_{dis}	$\overline{\text{OE}}$	A									ns
		B									

operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd}	Power dissipation capacitance	Outputs enabled				pF
		Outputs disabled				

PRODUCT PREVIEW

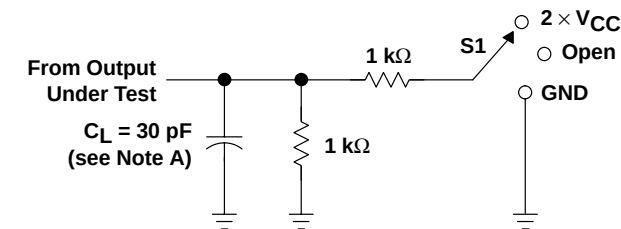


SN74ALVCH16280 16-BIT TO 32-BIT REGISTERED BUS EXCHANGER WITH BYTE MASKS AND 3-STATE OUTPUTS

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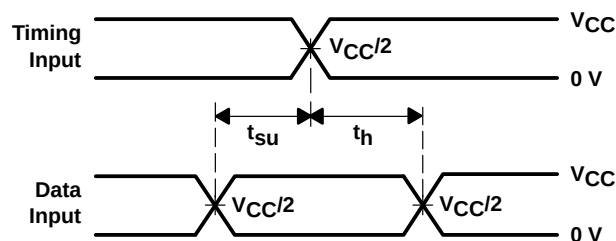
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8\text{ V}$

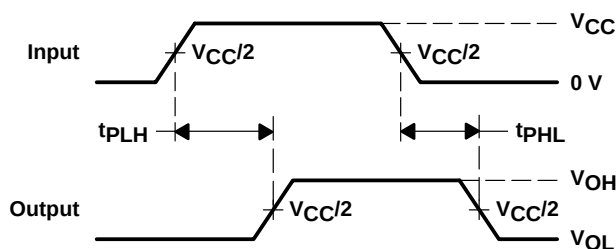


LOAD CIRCUIT

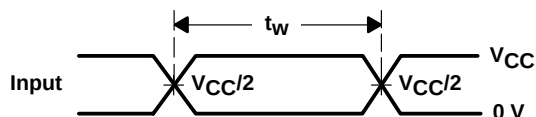
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times$ V_{CC}
t_{PHZ}/t_{PZH}	GND



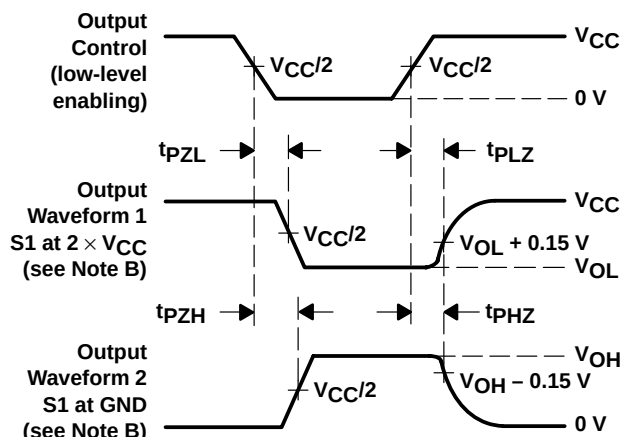
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



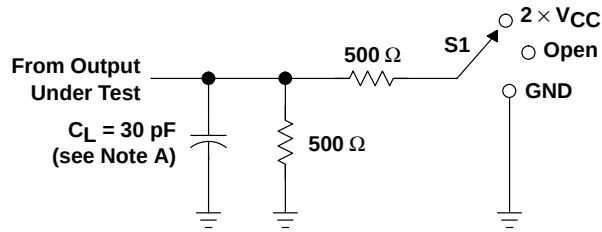
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

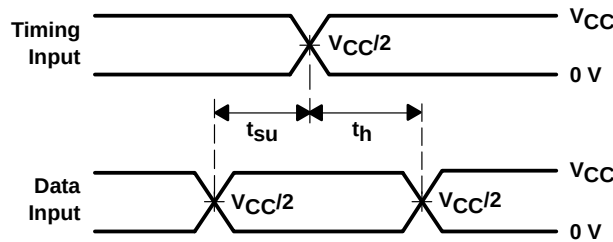
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

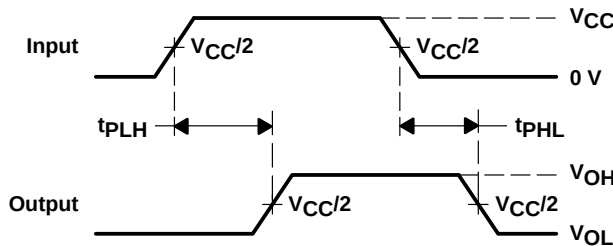


LOAD CIRCUIT

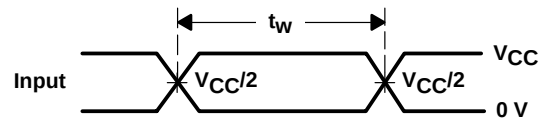
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



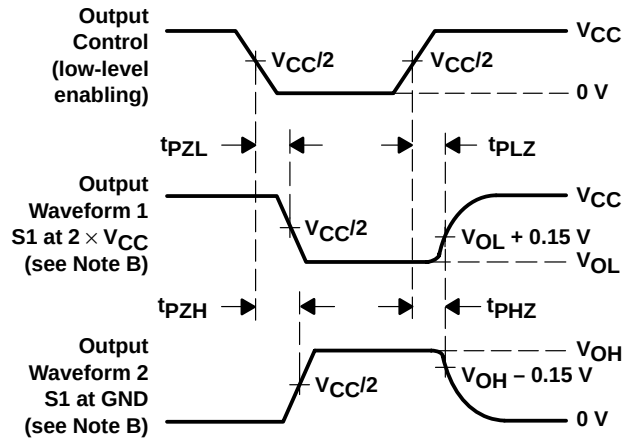
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

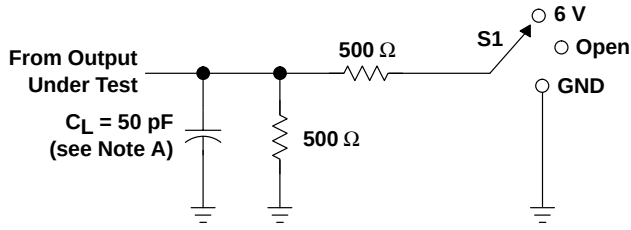
Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH16280 16-BIT TO 32-BIT REGISTERED BUS EXCHANGER WITH BYTE MASKS AND 3-STATE OUTPUTS

SCES033A – JULY 1995 – REVISED FEBRUARY 1999

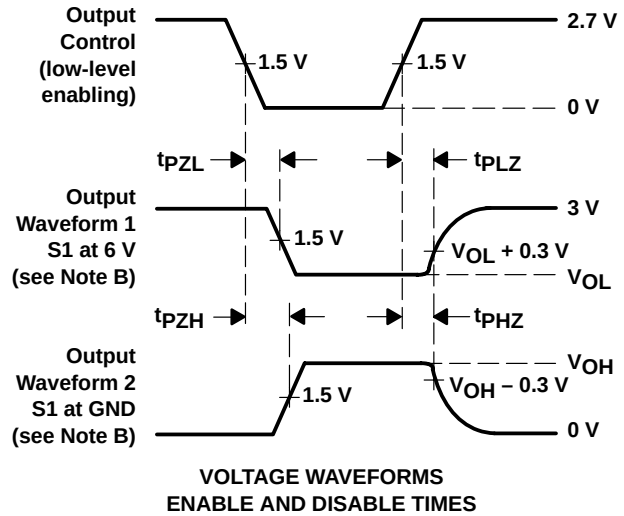
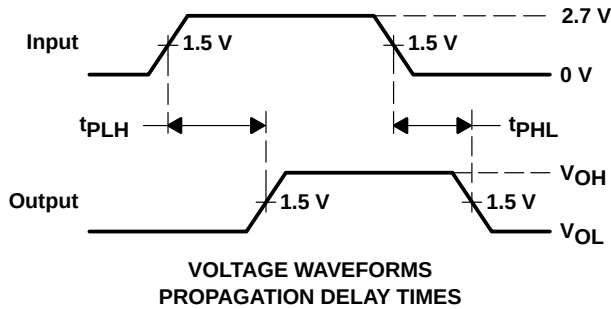
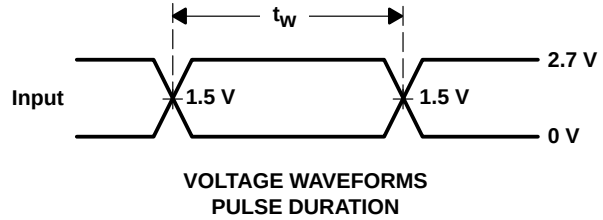
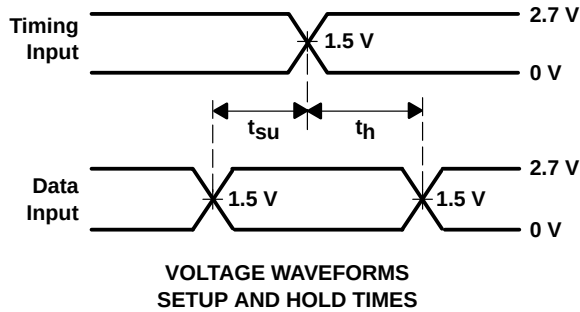
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16282

18-BIT TO 36-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

SCES036C – JULY 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Packaged in Thin Very Small-Outline Package

description

The SN74ALVCH16282 is an 18-bit to 36-bit registered bus exchanger designed for 1.65-V to 3.6-V V_{CC} operation.

This part is intended for use in applications in which data must be transferred from a narrow high-speed bus to a wide lower-frequency bus. It is designed specifically for low-voltage (3.3-V) V_{CC} operation.

The device provides synchronous data exchange between the two ports. Data is stored in the internal registers on the low-to-high transition of the clock (CLK) input. For data transfer in the B-to-A direction, the select ($\overline{SEL}$) input selects 1B or 2B data for the A outputs.

For data transfer in the A-to-B direction, a two-stage pipeline is provided in the 1B path, with a single storage register in the 2B path. Data flow is controlled by the active-low output enable ($\overline{OE}$) and the DIR input. The DIR control pin is registered to synchronize the bus direction changes with the clock.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16282 is characterized for operation from -40°C to 85°C .

DBB PACKAGE (TOP VIEW)

V_{CC}	1	80	V_{CC}
GND	2	79	GND
2B9	3	78	1B10
1B9	4	77	2B10
2B8	5	76	1B11
GND	6	75	GND
1B8	7	74	2B11
2B7	8	73	1B12
1B7	9	72	2B12
V_{CC}	10	71	V_{CC}
2B6	11	70	1B13
1B6	12	69	2B13
2B5	13	68	1B14
1B5	14	67	2B14
GND	15	66	GND
2B4	16	65	1B15
1B4	17	64	2B15
2B3	18	63	1B16
1B3	19	62	2B16
V_{CC}	20	61	V_{CC}
GND	21	60	GND
2B2	22	59	1B17
1B2	23	58	2B17
2B1	24	57	1B18
1B1	25	56	2B18
V_{CC}	26	55	V_{CC}
A1	27	54	A18
A2	28	53	A17
A3	29	52	A16
GND	30	51	GND
A4	31	50	A15
A5	32	49	A14
A6	33	48	A13
V_{CC}	34	47	V_{CC}
A7	35	46	A12
A8	36	45	A11
A9	37	44	A10
GND	38	43	GND
CLK	39	42	$\overline{OE}$
$\overline{SEL}$	40	41	DIR

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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SN74ALVCH16282

18-BIT TO 36-BIT REGISTERED BUS EXCHANGER

WITH 3-STATE OUTPUTS

SCES036C – JULY 1995 – REVISED FEBRUARY 1999

Function Tables

A-TO-B STORAGE ($\overline{OE} = L, DIR = H$)

INPUTS			OUTPUTS	
SEL	CLK	A	1B	2B
H	X	X	1B ₀ [†]	2B ₀ [†]
L	↑	L	L [‡]	X
L	↑	H	H [‡]	X

[†] Output level before indicated steady-state input conditions were established

[‡] Two CLK edges are needed to propagate the data.

B-TO-A STORAGE ($\overline{OE} = L, DIR = L$)

INPUTS				OUTPUT A
CLK	SEL	1B	2B	
↑	H	X	L	L [§]
↑	H	X	H	H [§]
↑	L	L	X	L
↑	L	H	X	H

[§] Two CLK edges are needed to propagate the data. The data is loaded in the first register when SEL is low and propagates to the second register when SEL is high.

OUTPUT ENABLE

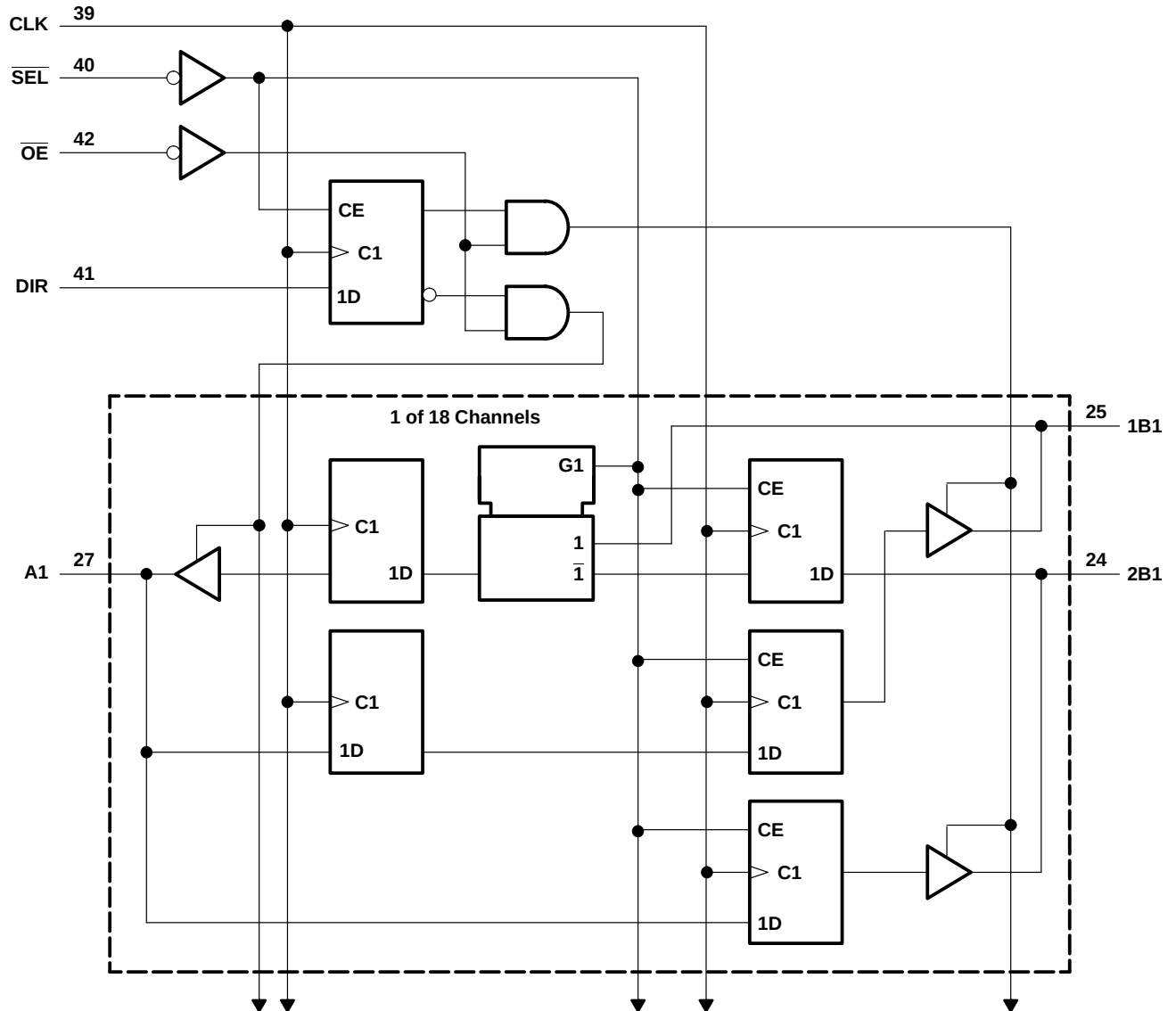
INPUTS			OUTPUTS	
CLK	$\overline{OE}$	DIR	A	1B, 2B
↑	H	X	Z	Z
↑	L	L	Z	Active
↑	L	H	Active	Z

SN74ALVCH16282

18-BIT TO 36-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

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logic diagram (positive logic)



SN74ALVCH16282

18-BIT TO 36-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3)	106°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



SN74ALVCH16282
18-BIT TO 36-BIT REGISTERED BUS EXCHANGER
WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ} [§]	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V		4	pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V		8.5	pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.

SN74ALVCH16282

18-BIT TO 36-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency		†		150		150		150		MHz
t _w	Pulse duration, CLK high or low		†		3.3		3.3		3.3		ns
t _{su}	Setup time	A data before CLK↑	†		2.4		2.3		2		ns
		B data before CLK↑	†		2.2		2.2		1.8		
		DIR before CLK↑	†		2.2		2.1		1.7		
		SEL before CLK↑	†		2		2		1.8		
t _h	Hold time	A data after CLK↑	†		0.5		0.5		0.7		ns
		B data after CLK↑	†		0.5		0.5		0.6		
		DIR after CLK↑	†		0.5		0.5		0.5		
		SEL after CLK↑	†		0.7		0.7		0.8		

† This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 1.8\text{ V}$		$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f_{max}			†		150		150		150		MHz
t_{pd}	CLK	A	†		1	6.1	5.5		1.4	5	ns
		B	†		1.2	6.3	5.7		1.6	5.3	
t_{en}	$\overline{\text{OE}}$	A	†		1.3	6.9	6.3		1.2	5.7	ns
		B	†		2.3	8.7	8.1		2.3	7.4	
t_{dis}	$\overline{\text{OE}}$	A	†		1.5	7	5.6		1.8	5.7	ns
		B	†		2.1	7.9	6.4		2.3	6.4	

† This information was not available at the time of publication.

operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd}	Power dissipation capacitance	$C_L = 0, f = 10\text{ MHz}$	†	282	310	pF
	Outputs disabled		†	208	228	

† This information was not available at the time of publication.



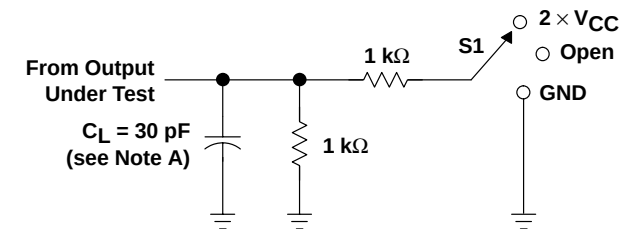
SN74ALVCH16282

18-BIT TO 36-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

SCES036C – JULY 1995 – REVISED FEBRUARY 1999

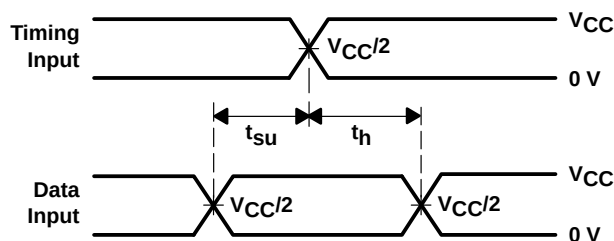
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$

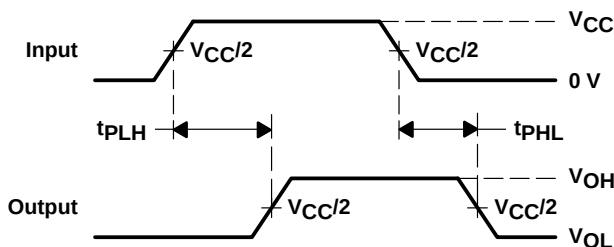


LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



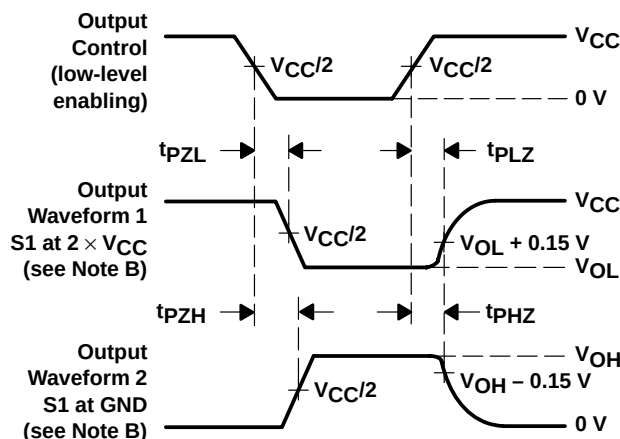
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH16282

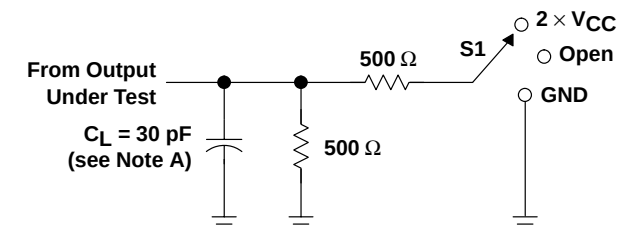
18-BIT TO 36-BIT REGISTERED BUS EXCHANGER

WITH 3-STATE OUTPUTS

SCES036C – JULY 1995 – REVISED FEBRUARY 1999

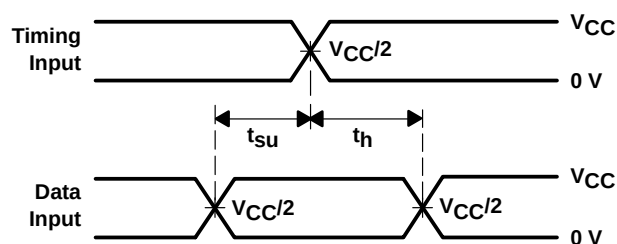
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

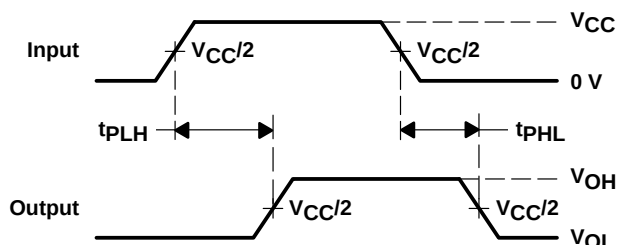


LOAD CIRCUIT

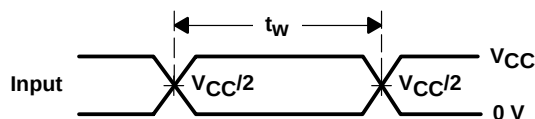
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



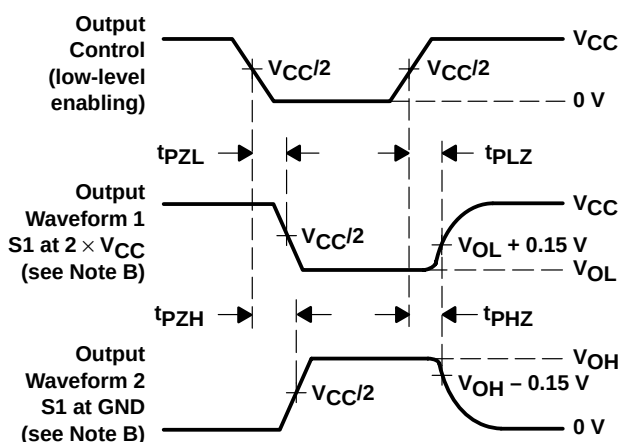
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

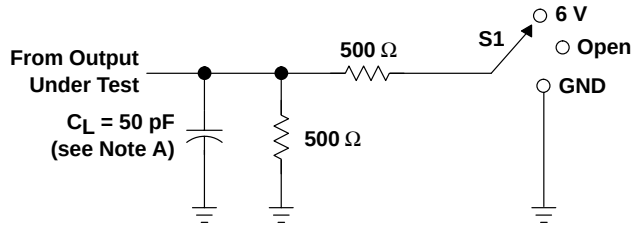
SN74ALVCH16282

18-BIT TO 36-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

SCES036C – JULY 1995 – REVISED FEBRUARY 1999

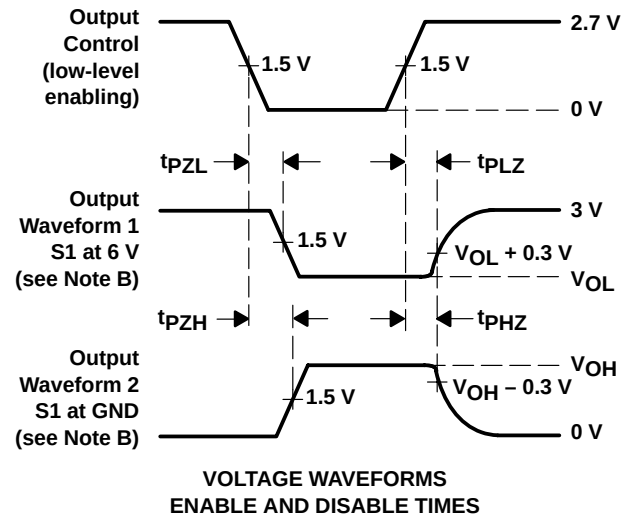
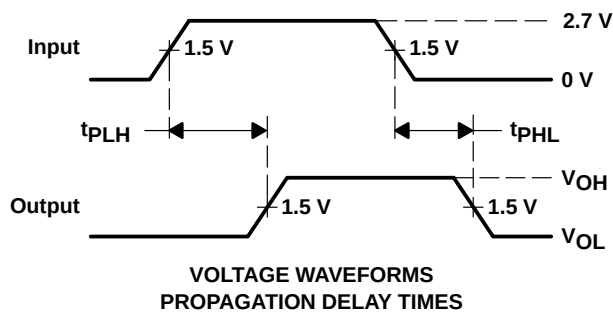
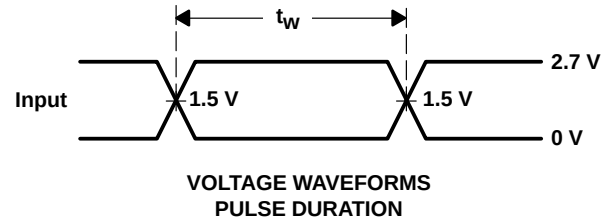
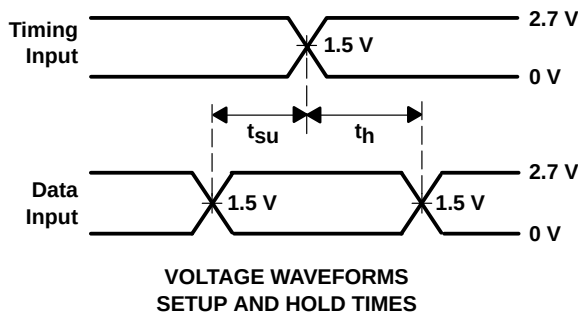
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V}$ AND $3.3 \text{ V} \pm 0.3 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dLZ} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVC16334

16-BIT UNIVERSAL BUS DRIVER WITH 3-STATE OUTPUTS

SCES128C – FEBRUARY 1998 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- Ideal for Use in PC100 Register DIMM
- Designed to Comply With JEDEC 168-Pin and 200-Pin SDRAM Buffered DIMM Specification
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Package Options Include Plastic Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages

description

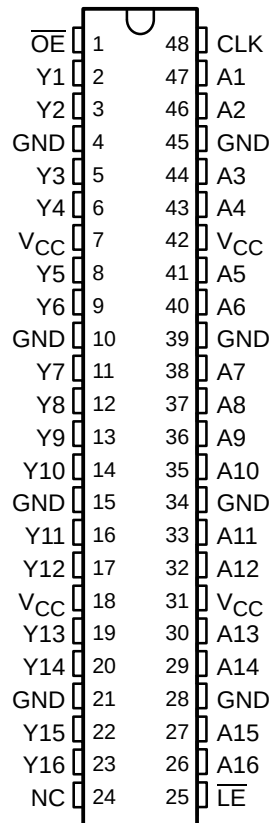
This 16-bit universal bus driver is designed for 1.65-V to 3.6-V V_{CC} operation.

Data flow from A to Y is controlled by the output-enable ($\overline{OE}$) input. The device operates in the transparent mode when the latch-enable ($\overline{LE}$) input is low. When $\overline{LE}$ is high, the A data is latched if the clock (CLK) input is held at a high or low logic level. If $\overline{LE}$ is high, the A data is stored in the latch/flip-flop on the low-to-high transition of CLK. When $\overline{OE}$ is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74ALVC16334 is characterized for operation from -40°C to 85°C .

DGG, DGV, OR DL PACKAGE (TOP VIEW)



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SN74ALVC16334
16-BIT UNIVERSAL BUS DRIVER
WITH 3-STATE OUTPUTS

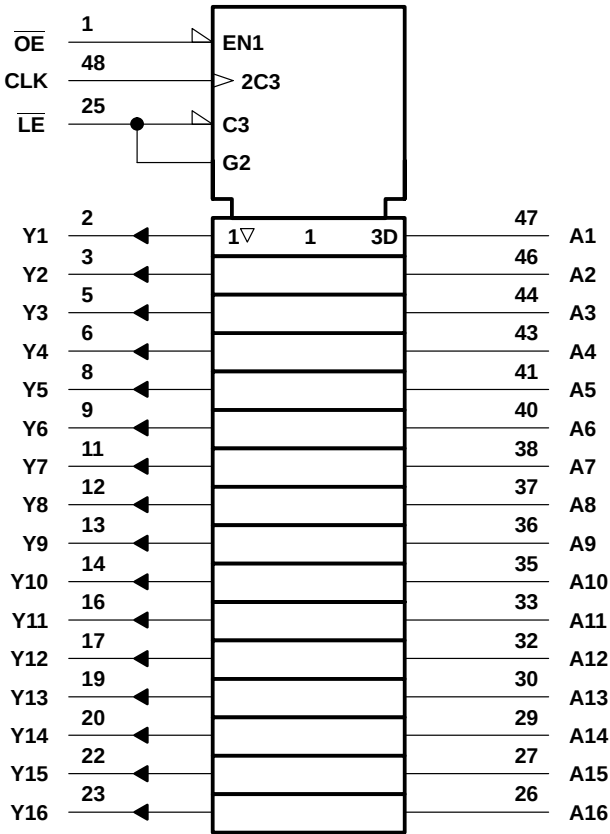
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FUNCTION TABLE

INPUTS				OUTPUT Y
OE	LE	CLK	A	
H	X	X	X	Z
L	L	X	L	L
L	L	X	H	H
L	H	↑	L	L
L	H	↑	H	H
L	H	L or H	X	Y ₀ [†]

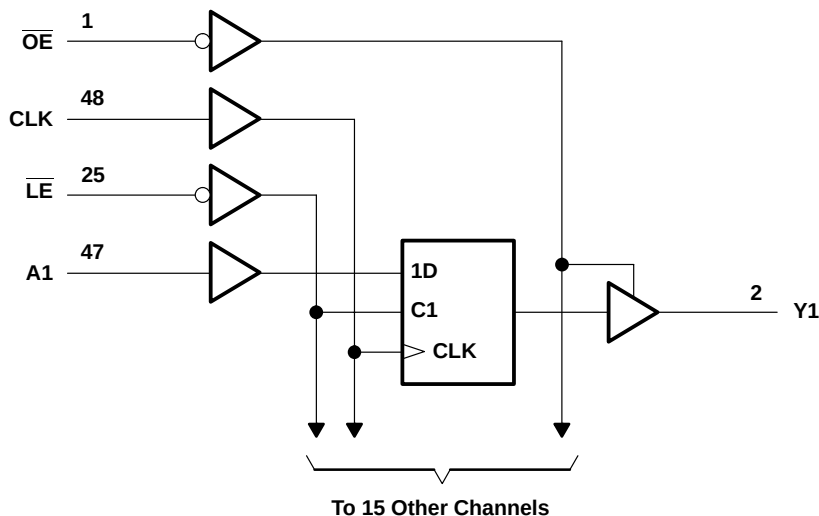
† Output level before the indicated steady-state input conditions were established

logic symbol[‡]



[‡] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3):	
DGG package	89°C/W
DGV package	93°C/W
DL package	94°C/W
Storage temperature range, T_{Stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–4	mA
		$V_{CC} = 2.3 \text{ V}$	–12	
		$V_{CC} = 2.7 \text{ V}$	–12	
		$V_{CC} = 3 \text{ V}$	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	4	mA
		$V_{CC} = 2.3 \text{ V}$	12	
		$V_{CC} = 2.7 \text{ V}$	12	
		$V_{CC} = 3 \text{ V}$	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
		I _{OL} = 12 mA	2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	5			pF
	Data inputs			5.5			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT	
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
f _{clock}	Clock frequency		‡		150		150		150		MHz	
t _w	Pulse duration	LE low		‡		3.3		3.3		3.3		ns
		CLK high or low		‡		3.3		3.3		3.3		
t _{su}	Setup time	Data before CLK↑		‡		1.4		1.7		1.5		ns
		Data before LE↑	CLK high	‡		1.2		1.6		1.3		
			CLK low	‡		1.4		1.5		1.2		
t _h	Hold time	Data after CLK↑		‡		0.9		0.9		0.9		ns
		Data after LE↑	CLK high or low	‡		1.1		1.1		1.1		

‡ This information was not available at the time of publication.



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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	A	Y	†		1	3.7	3.6		1.1	3.3	ns
	$\overline{LE}$		†		1	4.8	5		1.3	4.4	
	CLK		†		1	4.4	4.5		1	4.1	
t _{en}	$\overline{OE}$	Y	†		1	5.4	5.4		1.1	4.6	ns
t _{dis}	$\overline{OE}$	Y	†		1	4.1	4.5		1.7	4.4	ns

† This information was not available at the time of publication.

switching characteristics from 0°C to 65°C, C_L = 50 pF

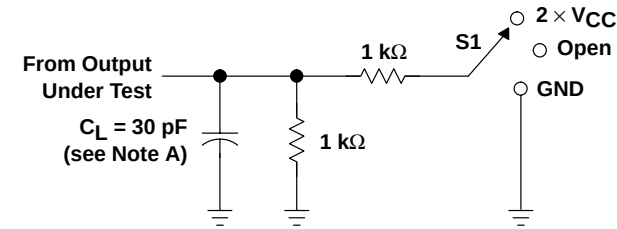
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 3.3 V ± 0.15 V		UNIT
			MIN	MAX	
t _{pd}	A	Y	1.2	3.2	ns
	CLK	Y	1.1	4	ns

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 0, f = 10 MHz	†	31	36	pF
		Outputs disabled		†	7	11	

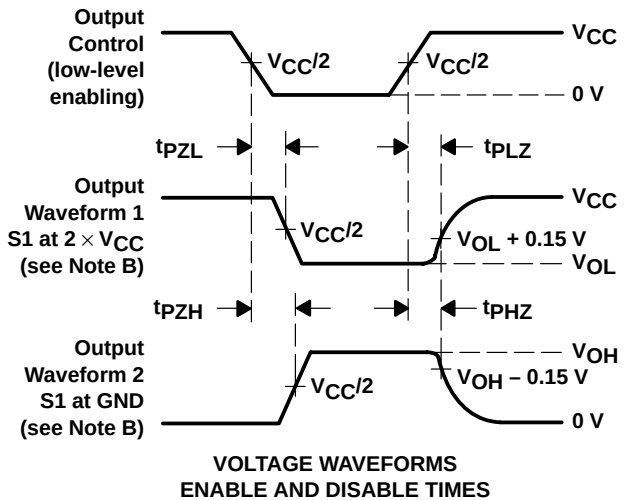
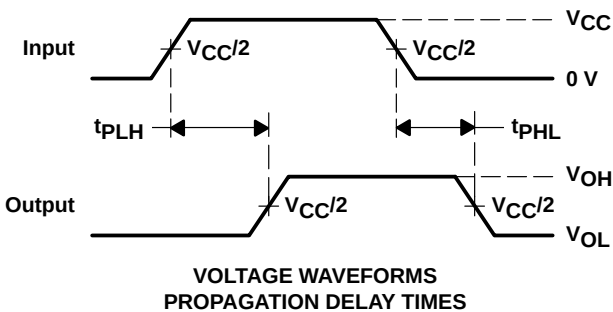
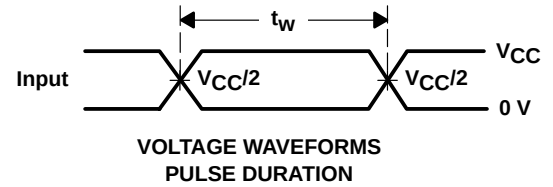
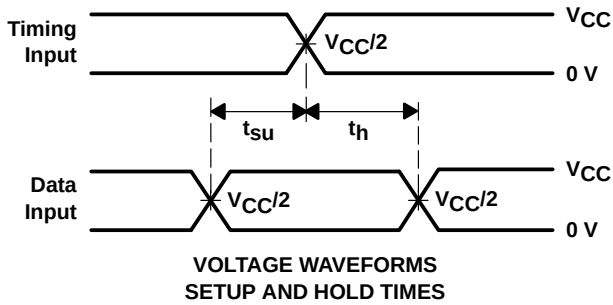
† This information was not available at the time of publication.

PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	$2 \times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

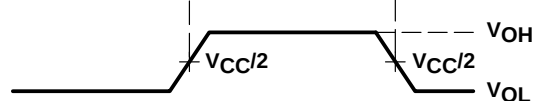
Figure 1. Load Circuit and Voltage Waveforms

WITH 3-STATE OUTPUTS

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$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$
 $\times V_C$ 

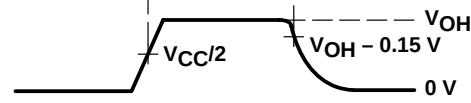
SETUP AND HOLD TIMES



PROPAGATION DELAY TIMES



PULSE DURATION



ENABLE AND DISABLE TIMES

NOTES: A. C_1 includes probe and jig capacitance.

Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control

C. All input pulses are supplied by generators having the following characteristics: $\text{PRR} \leq 10 \text{ MHz}$, $Z_0 = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.

D. The outputs are measured one at a time with one transition per measurement.

E. t_{pL7} and t_{pH7} are the same as t_{dis} .

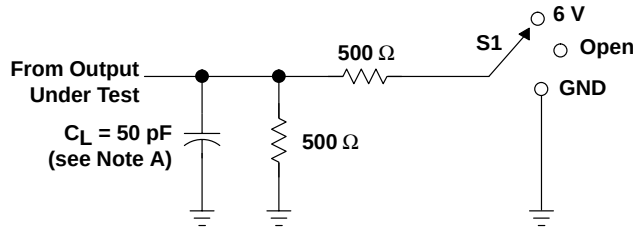
F. tp_{7I} and tp_{7H} are the same as t_{en} .

G. $t_{p|H}$ and $t_{pH|}$ are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

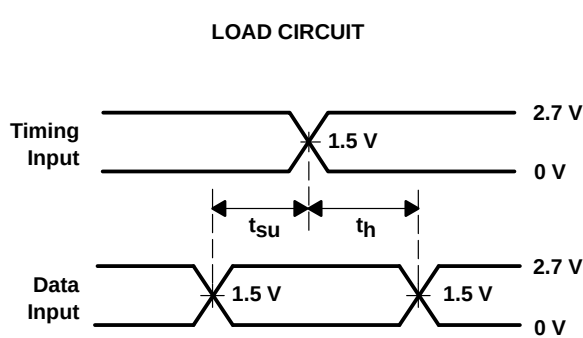
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

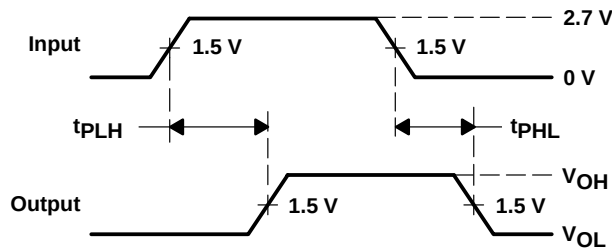


LOAD CIRCUIT

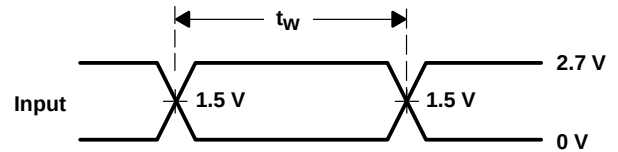
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



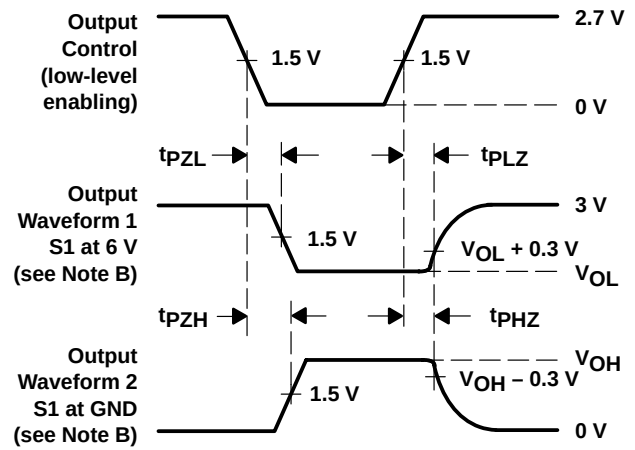
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES: A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
- D. The outputs are measured one at a time with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16334

16-BIT UNIVERSAL BUS DRIVER WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- Designed to Comply With JEDEC 168-Pin and 200-Pin SDRAM Buffered DIMM Specification
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages

description

This 16-bit universal bus driver is designed for 1.65-V to 3.6-V V_{CC} operation.

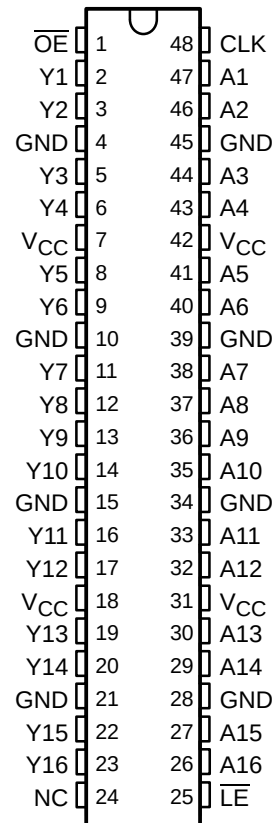
Data flow from A to Y is controlled by the output-enable ($\overline{OE}$) input. The device operates in the transparent mode when the latch-enable ($\overline{LE}$) input is low. When $\overline{LE}$ is high, the A data is latched if the clock (CLK) input is held at a high or low logic level. If $\overline{LE}$ is high, the A data is stored in the latch/flip-flop on the low-to-high transition of CLK. When $\overline{OE}$ is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16334 is characterized for operation from -40°C to 85°C .

DGG, DGV, OR DL PACKAGE (TOP VIEW)



NC – No internal connection

EPIC and Widebus are trademarks of Texas Instruments Incorporated.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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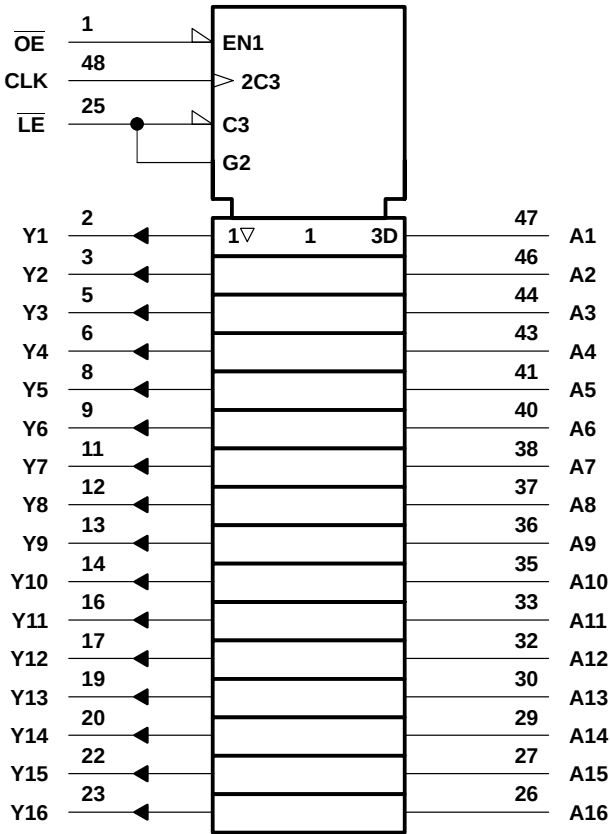
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FUNCTION TABLE

INPUTS				OUTPUT Y
OE	LE	CLK	A	
H	X	X	X	Z
L	L	X	L	L
L	L	X	H	H
L	H	↑	L	L
L	H	↑	H	H
L	H	L or H	X	Y ₀ [†]

† Output level before the indicated steady-state input conditions were established

logic symbol[‡]



[‡] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

The diagram illustrates the logic for a 16-channel 1D/2D data acquisition system. It features four input channels: $\overline{OE}$ (1), CLK (48), $\overline{LE}$ (25), and A1 (47). These inputs are connected to a central 1D/2D data acquisition block. The block has inputs 1D, C1, and CLK. The output of the block is connected to a 2-bit output Y1. The diagram also shows connections to 15 other channels, indicated by a bracket labeled "To 15 Other Channels".

Supply voltage range, V_{CC}		-0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)		-0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)		-0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)		-50 mA
Output clamp current, I_{OK} ($V_O < 0$)		-50 mA
Continuous output current, I_O		± 50 mA
Continuous current through each V_{CC} or GND		± 100 mA
Package thermal impedance, θ_{JA} (see Note 3):		
DGG package		89°C/W
DGV package		93°C/W
DL package		94°C/W
Storage temperature range, T_{stg}		-65°C to 150°C

NOTES:

1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–4	mA
		$V_{CC} = 2.3 \text{ V}$	–12	
		$V_{CC} = 2.7 \text{ V}$	–12	
		$V_{CC} = 3 \text{ V}$	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	4	mA
		$V_{CC} = 2.3 \text{ V}$	12	
		$V_{CC} = 2.7 \text{ V}$	12	
		$V_{CC} = 3 \text{ V}$	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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16-BIT UNIVERSAL BUS DRIVER
WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
		I _{OL} = 12 mA	2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	5.5			pF
	Data inputs			6			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	8			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.



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16-BIT UNIVERSAL BUS DRIVER

WITH 3-STATE OUTPUTS

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

				V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
				MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency			†		150		150		150		MHz
t _w	Pulse duration	LE low		†		3.3		3.3		3.3		ns
		CLK high or low		†		3.3		3.3		3.3		
t _{su}	Setup time	Data before CLK↑		†		1.4		1.7		1.5		ns
		Data before LE↑	CLK high	†		1.2		1.6		1.3		
			CLK low	†		1.4		1.5		1.2		
t _h	Hold time	Data after CLK↑		†		0.9		0.8		0.9		ns
		Data after LE↑	CLK high or low	†		1.2		1.1		1.1		

† This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	A	Y	†		1	3.7	3.6		1.1	3.3	ns
	$\overline{LE}$		†		1	4.8	5		1.3	4.4	
	CLK		†		1	4.4	4.5		1	4.1	
t _{en}	$\overline{OE}$	Y	†		1	5.4	5.4		1.1	4.6	ns
t _{dis}	$\overline{OE}$	Y	†		1	4.1	4.5		1.7	4.4	ns

† This information was not available at the time of publication.

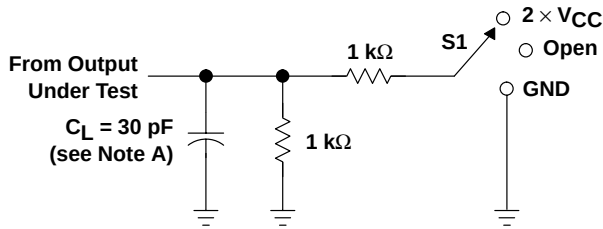
operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 0, f = 10 MHz	†	32	37	pF
		Outputs disabled		†	7	11	

† This information was not available at the time of publication.

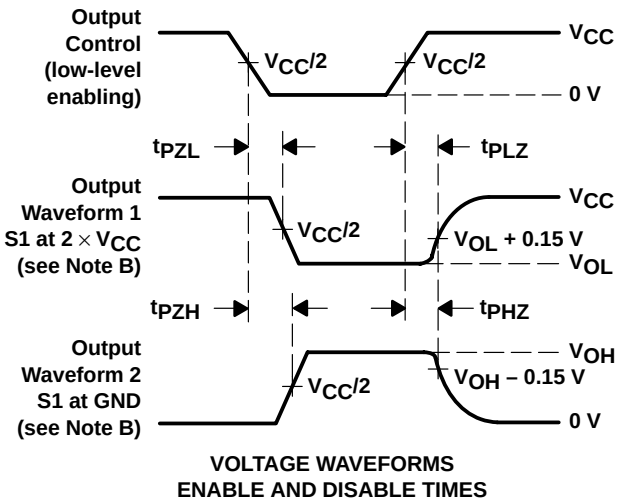
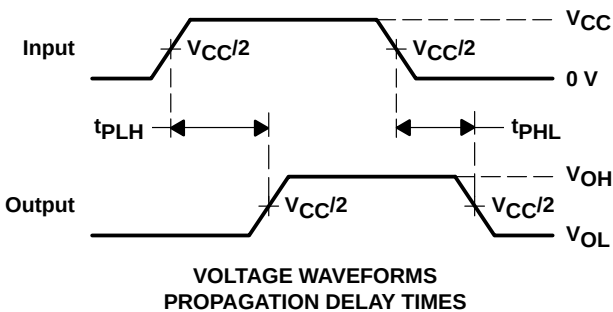
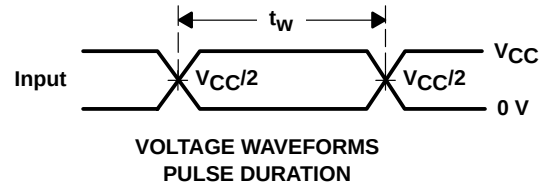
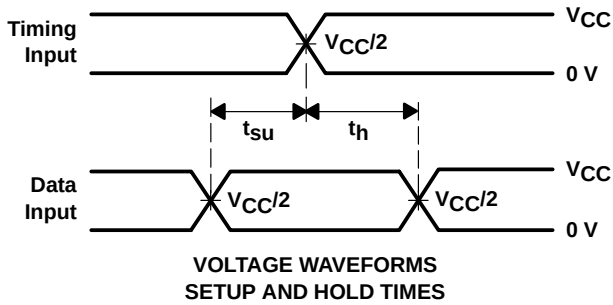


PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH16334

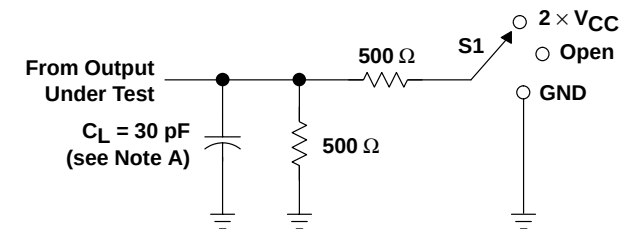
16-BIT UNIVERSAL BUS DRIVER

WITH 3-STATE OUTPUTS

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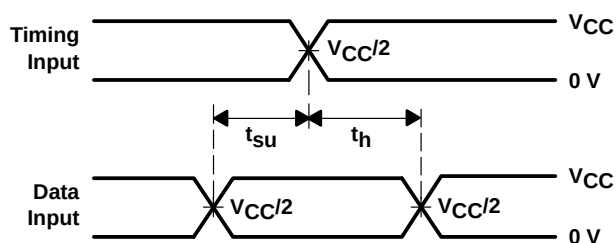
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

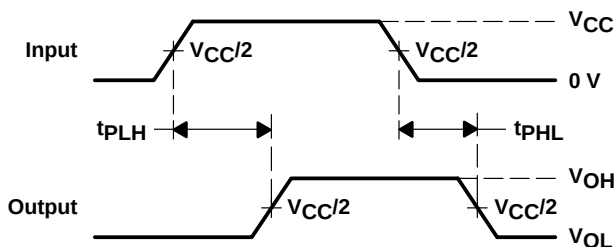


LOAD CIRCUIT

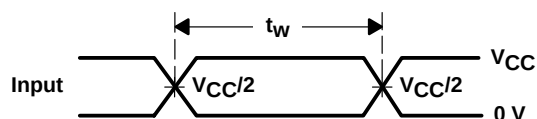
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



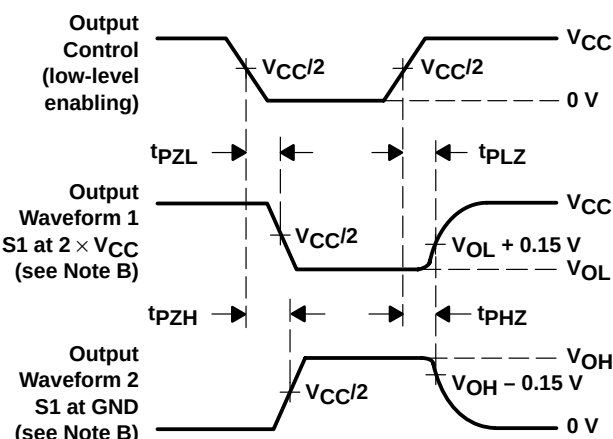
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



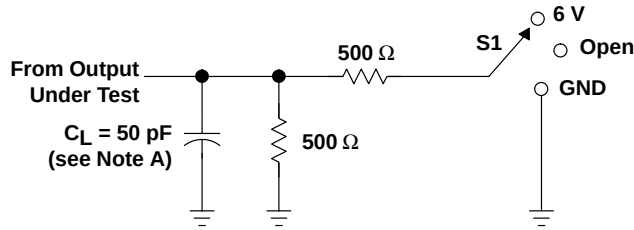
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

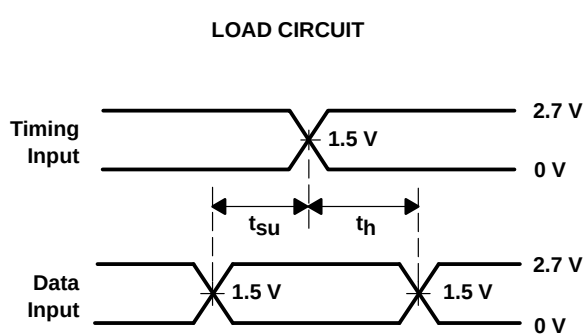
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

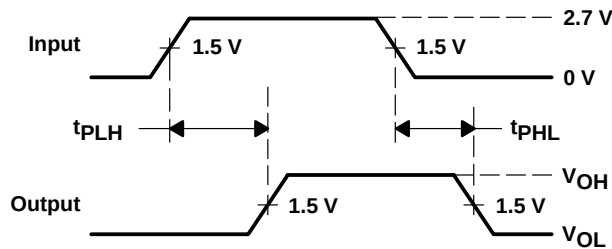


LOAD CIRCUIT

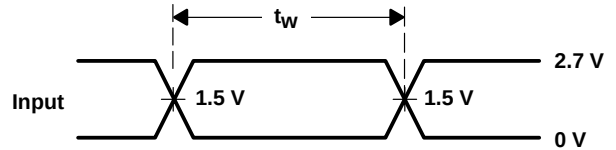
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



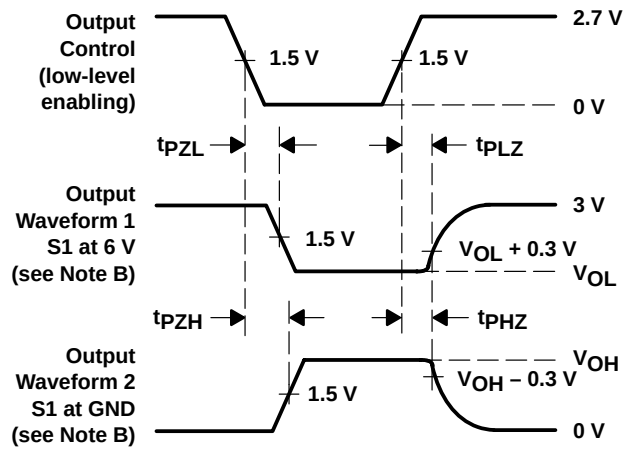
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16344

1-BIT TO 4-BIT ADDRESS DRIVER WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages

description

This 1-bit to 4-bit address driver is designed for 1.65-V to 3.6-V V_{CC} operation.

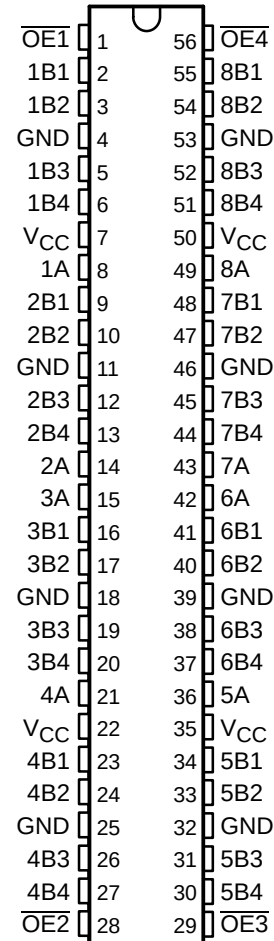
The SN74ALVCH16344 is used in applications in which four separate memory locations must be addressed by a single address.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating inputs at a valid logic level.

The SN74ALVCH16344 is characterized for operation from -40°C to 85°C .

DGG, DGV, OR DL PACKAGE
(TOP VIEW)



FUNCTION TABLE

INPUTS		OUTPUT Bn
$\overline{OE}$	A	
L	H	H
L	L	L
H	H	Z

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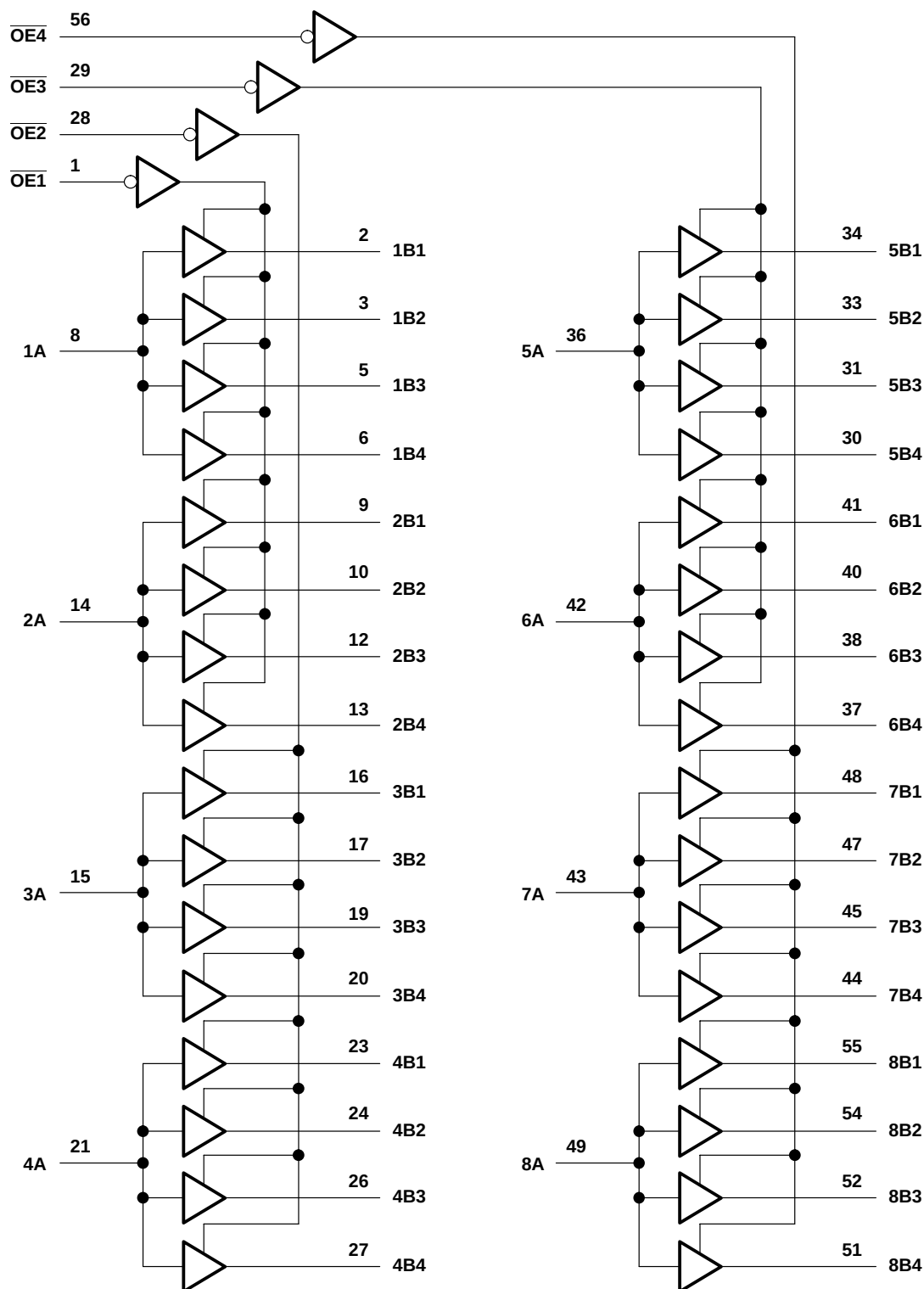
SN74ALVCH16344

1-BIT TO 4-BIT ADDRESS DRIVER

WITH 3-STATE OUTPUTS

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logic diagram (positive logic)



Supply voltage range, V_{CC}	−0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	−0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	−0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	−50 mA
Output clamp current, I_{OK} ($V_O < 0$)	−50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DGV package	86°C/W
DL package	74°C/W

NOTES:

1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate		10		ns/V
T _A	Operating free-air temperature		−40	85	°C



**1-BIT TO 4-BIT ADDRESS DRIVER
WITH 3-STATE OUTPUTS**

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} – 0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	2.5			pF
	Data inputs		3.5			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V		4	pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	B	§	1	4.6	4.6		1.4	4	ns
t _{en}	OE	B	§	1	6.2	6.2		1.2	5.1	ns
t _{dis}	OE	B	§	1	5.1	4.4		1.2	4	ns
t _{sk(o)} [¶]								0.35		ns
t _{sk(o)} [#]								0.5		ns

[§] This information was not available at the time of publication.

[¶] Skew between outputs of same bank and same package (same transition).

[#] Skew between outputs of all banks and same package (A1 through A8 tied together).

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1-BIT TO 4-BIT ADDRESS DRIVER WITH 3-STATE OUTPUTS

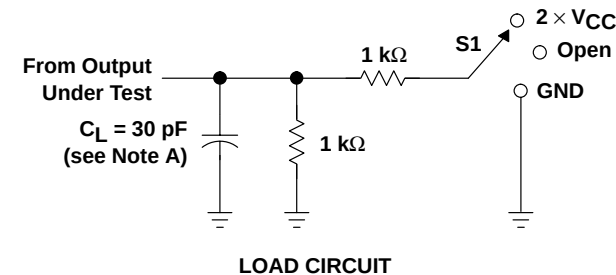
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operating characteristics, $T_A = 25^\circ\text{C}$

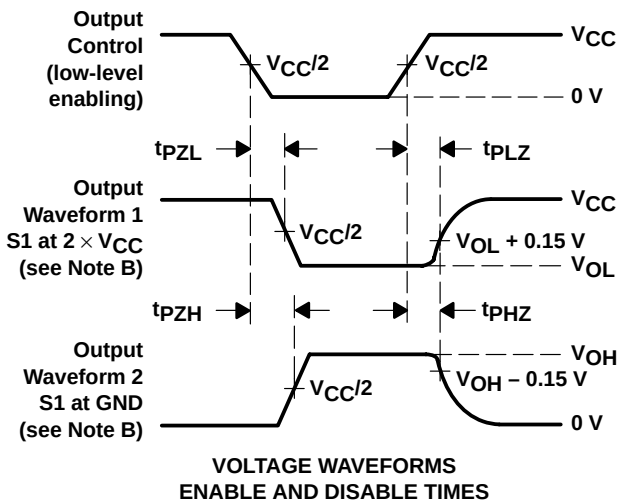
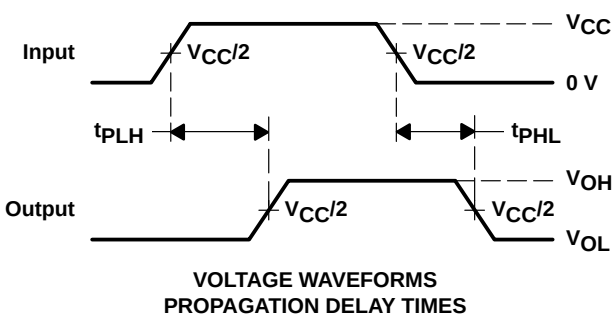
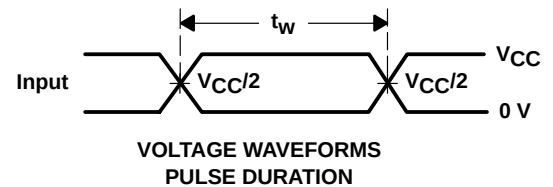
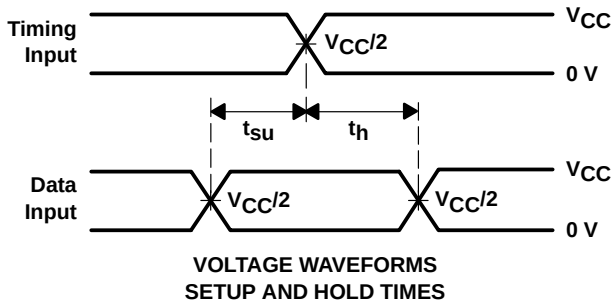
PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd} Power dissipation capacitance	Outputs enabled	$C_L = 50\text{ pF}, f = 10\text{ MHz}$	†	68	84	pF
	Outputs disabled		†	11	14	

† This information was not available at the time of publication.

PARAMETER MEASUREMENT INFORMATION $V_{CC} = 1.8\text{ V}$



TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms



SN74ALVCH16344

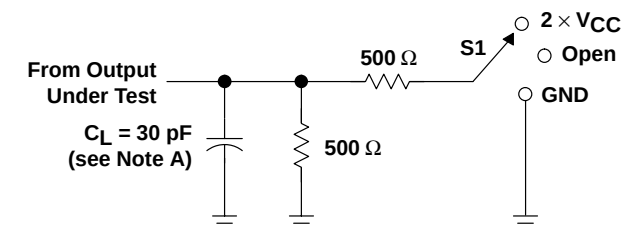
1-BIT TO 4-BIT ADDRESS DRIVER

WITH 3-STATE OUTPUTS

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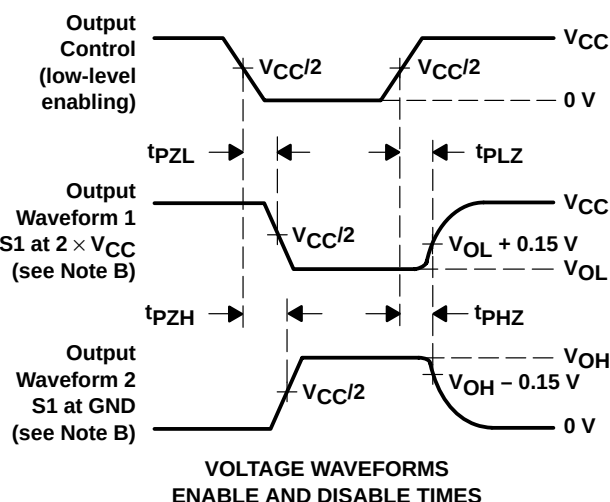
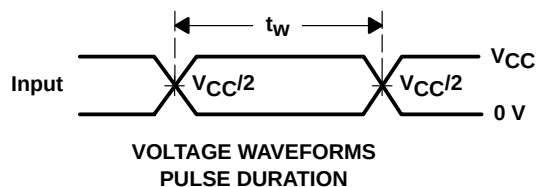
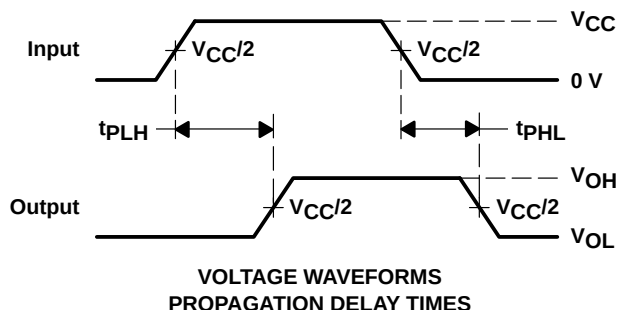
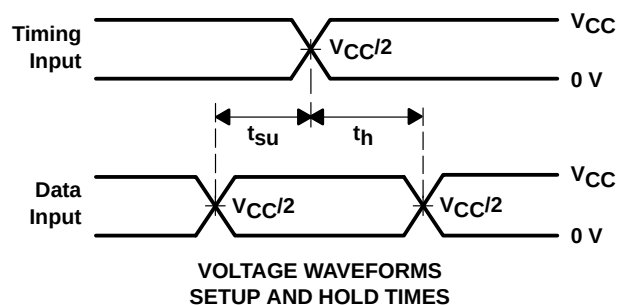
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PHL}	GND

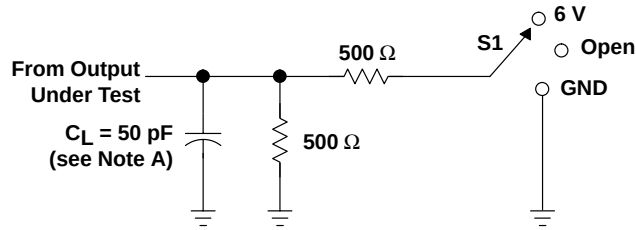


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

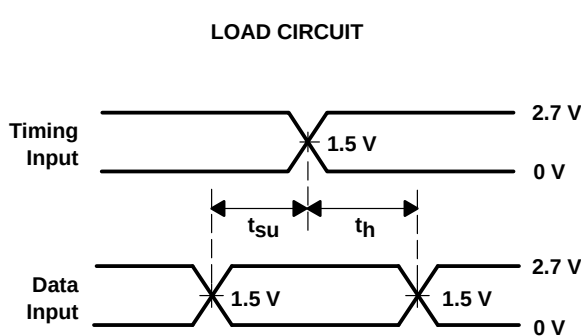
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V}$ AND $3.3\text{ V} \pm 0.3\text{ V}$

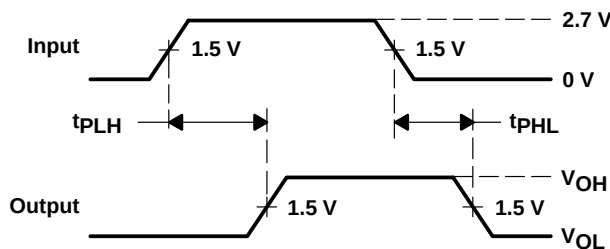


LOAD CIRCUIT

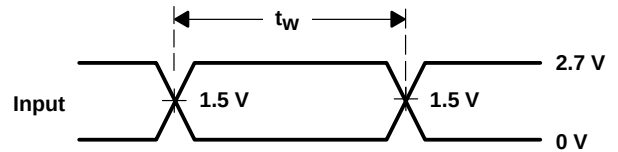
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



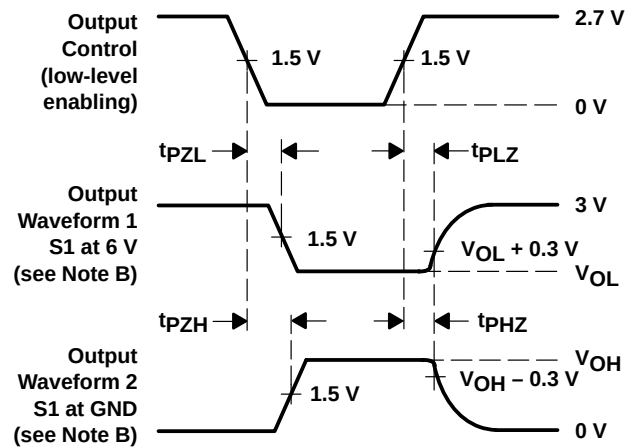
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16373

16-BIT TRANSPARENT D-TYPE LATCH WITH 3-STATE OUTPUTS

SCES020C – JULY 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883C, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 16-bit transparent D-type latch is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16373 is particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers. This device can be used as two 8-bit latches or one 16-bit latch. When the latch-enable (LE) input is high, the Q outputs follow the data (D) inputs. When LE is taken low, the Q outputs are latched at the levels set up at the D inputs.

A buffered output-enable ($\overline{OE}$) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and the increased drive provide the capability to drive bus lines without need for interface or pullup components. $\overline{OE}$ does not affect internal operations of the latch. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16373 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE (TOP VIEW)

$1\overline{OE}$	1	48	1LE
1Q1	2	47	1D1
1Q2	3	46	1D2
GND	4	45	GND
1Q3	5	44	1D3
1Q4	6	43	1D4
V_{CC}	7	42	V_{CC}
1Q5	8	41	1D5
1Q6	9	40	1D6
GND	10	39	GND
1Q7	11	38	1D7
1Q8	12	37	1D8
2Q1	13	36	2D1
2Q2	14	35	2D2
GND	15	34	GND
2Q3	16	33	2D3
2Q4	17	32	2D4
V_{CC}	18	31	V_{CC}
2Q5	19	30	2D5
2Q6	20	29	2D6
GND	21	28	GND
2Q7	22	27	2D7
2Q8	23	26	2D8
$2\overline{OE}$	24	25	2LE

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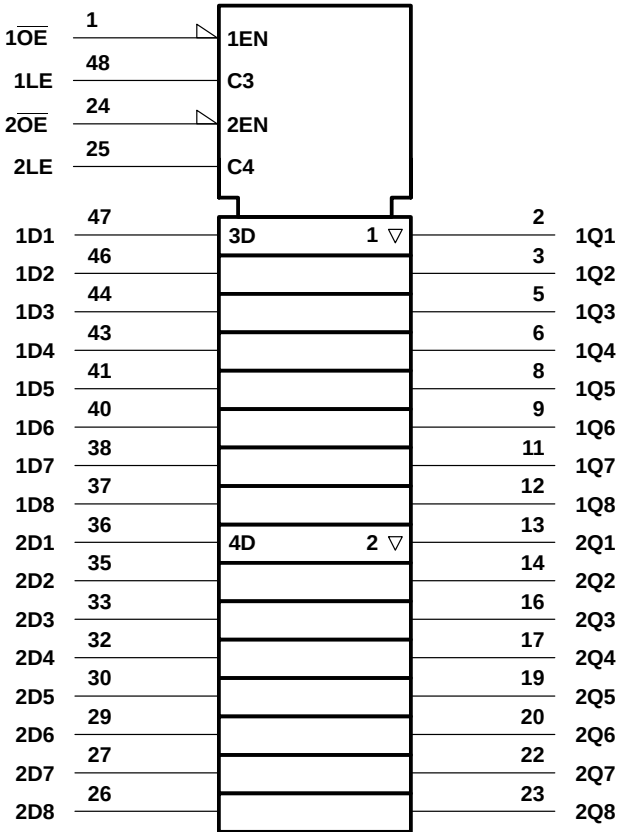
SN74ALVCH16373 16-BIT TRANSPARENT D-TYPE LATCH WITH 3-STATE OUTPUTS

SCES020C – JULY 1995 – REVISED FEBRUARY 1999

FUNCTION TABLE
(each 8-bit section)

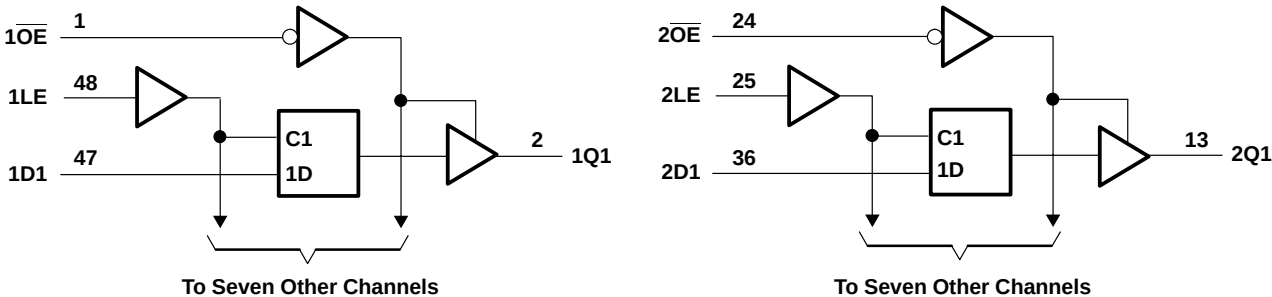
INPUTS			OUTPUT Q
$\overline{OE}$	LE	D	
L	H	H	H
L	H	L	L
L	L	X	Q ₀
H	X	X	Z

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



SN74ALVCH16373
16-BIT TRANSPARENT D-TYPE LATCH
WITH 3-STATE OUTPUTS

SCES020C – JULY 1995 – REVISED FEBRUARY 1999

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	89°C/W
DL package	94°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate			10	ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



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16-BIT TRANSPARENT D-TYPE LATCH

WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	3.3 V	3			pF
	Data inputs		6			
C _O	Outputs	3.3 V	7			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t _w	Pulse duration, LE high or low	§		3.3		3.3		3.3		ns
t _{su}	Setup time, data before LE↓	§		1		1		1.1		ns
t _h	Hold time, data after LE↓	§		1.5		1.7		1.4		ns

§ This information was not available at the time of publication.



SN74ALVCH16373
16-BIT TRANSPARENT D-TYPE LATCH
WITH 3-STATE OUTPUTS

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	D	Q	†	1	4.5	4.3		1.1	3.6	ns
	LE		†	1	4.9	4.6		1	3.9	
t _{en}	$\overline{\text{OE}}$	Q	†	1	6	5.7		1	4.7	ns
t _{dis}	$\overline{\text{OE}}$	Q	†	1.2	5.1	4.5		1.4	4.1	ns

† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 50 pF, f = 10 MHz	†	19	22	pF
		Outputs disabled		†	4	5	

† This information was not available at the time of publication.



SN74ALVCH16373

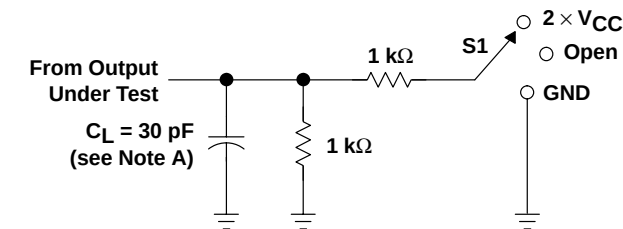
16-BIT TRANSPARENT D-TYPE LATCH

WITH 3-STATE OUTPUTS

SCES020C – JULY 1995 – REVISED FEBRUARY 1999

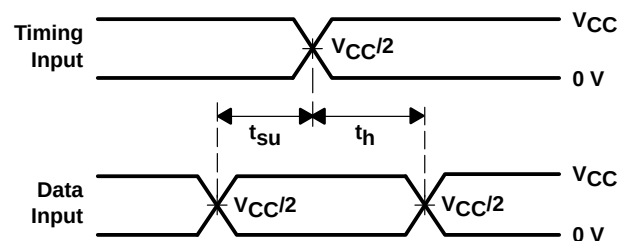
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$

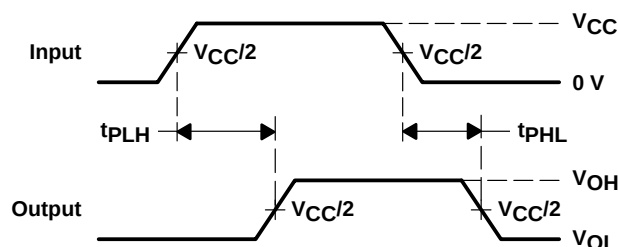


LOAD CIRCUIT

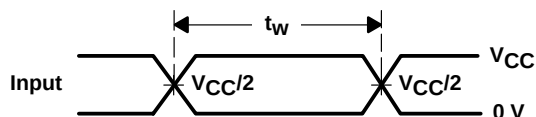
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



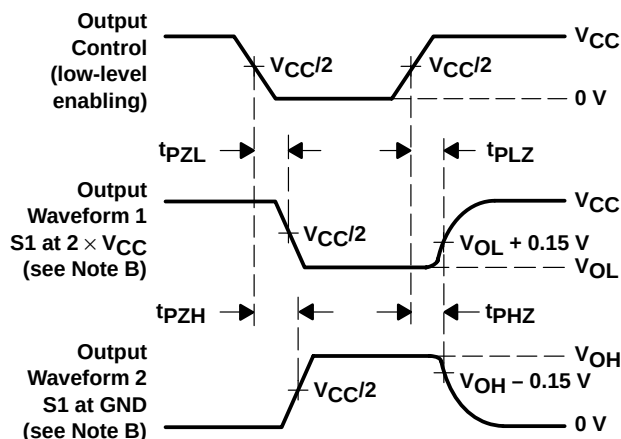
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



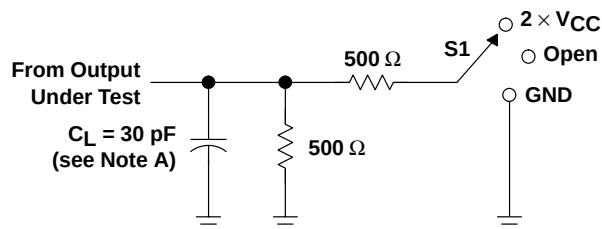
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

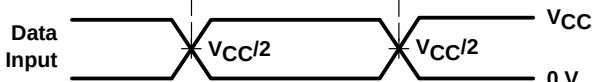
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

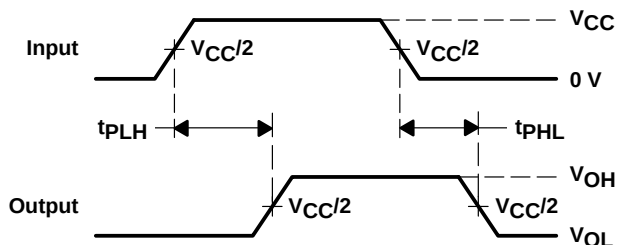


LOAD CIRCUIT

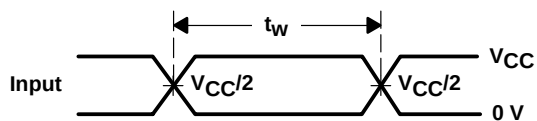
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times$ V_{CC}
t_{PHZ}/t_{PZH}	GND



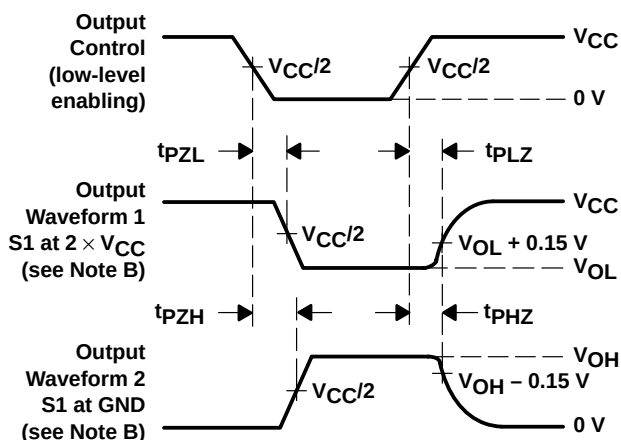
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH16373

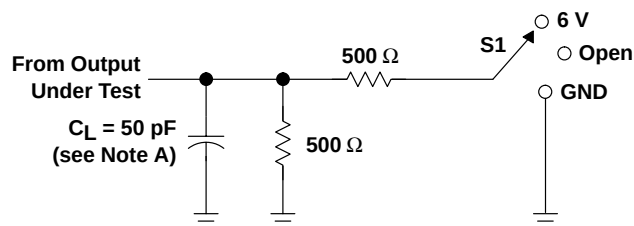
16-BIT TRANSPARENT D-TYPE LATCH

WITH 3-STATE OUTPUTS

SCES020C – JULY 1995 – REVISED FEBRUARY 1999

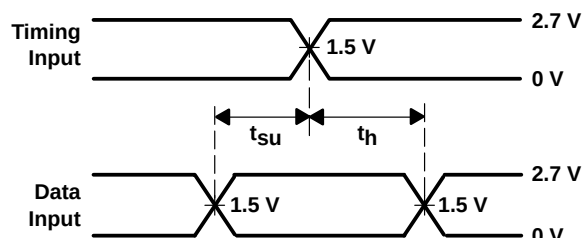
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$

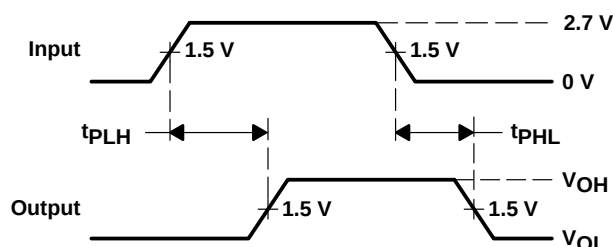


LOAD CIRCUIT

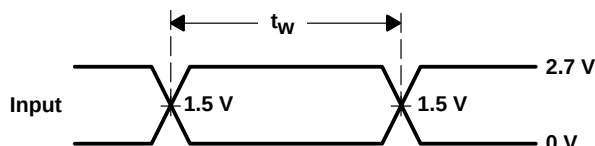
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



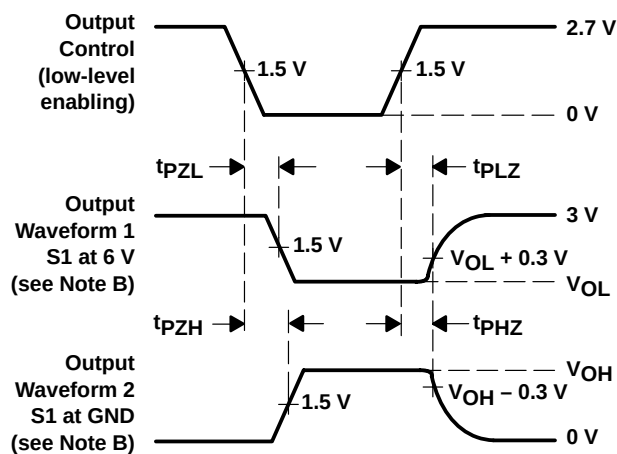
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16374

16-BIT EDGE-TRIGGERED D-TYPE FLIP-FLOP WITH 3-STATE OUTPUTS

SCES021D – JULY 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 16-bit edge-triggered D-type flip-flop is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16374 is particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers. It can be used as two 8-bit flip-flops or one 16-bit flip-flop. On the positive transition of the clock (CLK) input, the Q outputs of the flip-flop take on the logic levels at the data (D) inputs. $\overline{OE}$ can be used to place the eight outputs in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and the increased drive provide the capability to drive bus lines without need for interface or pullup components.

$\overline{OE}$ does not affect internal operations of the flip-flop. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16374 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)

$\overline{1OE}$	1	48	1CLK
1Q1	2	47	1D1
1Q2	3	46	1D2
GND	4	45	GND
1Q3	5	44	1D3
1Q4	6	43	1D4
V_{CC}	7	42	V_{CC}
1Q5	8	41	1D5
1Q6	9	40	1D6
GND	10	39	GND
1Q7	11	38	1D7
1Q8	12	37	1D8
2Q1	13	36	2D1
2Q2	14	35	2D2
GND	15	34	GND
2Q3	16	33	2D3
2Q4	17	32	2D4
V_{CC}	18	31	V_{CC}
2Q5	19	30	2D5
2Q6	20	29	2D6
GND	21	28	GND
2Q7	22	27	2D7
2Q8	23	26	2D8
$\overline{2OE}$	24	25	2CLK

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SN74ALVCH16374
16-BIT EDGE-TRIGGERED D-TYPE FLIP-FLOP
WITH 3-STATE OUTPUTS

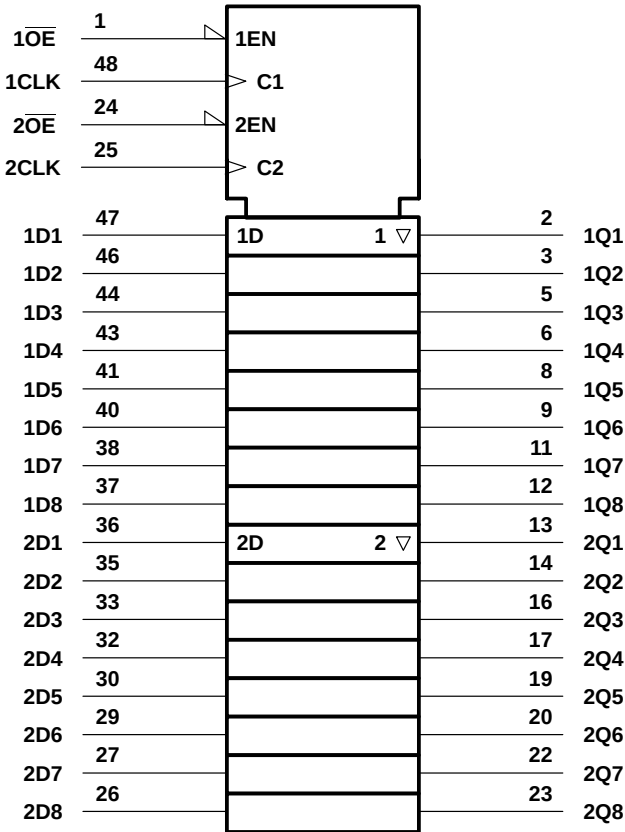
SCES021D – JULY 1995 – REVISED FEBRUARY 1999

FUNCTION TABLE

(each flip-flop)

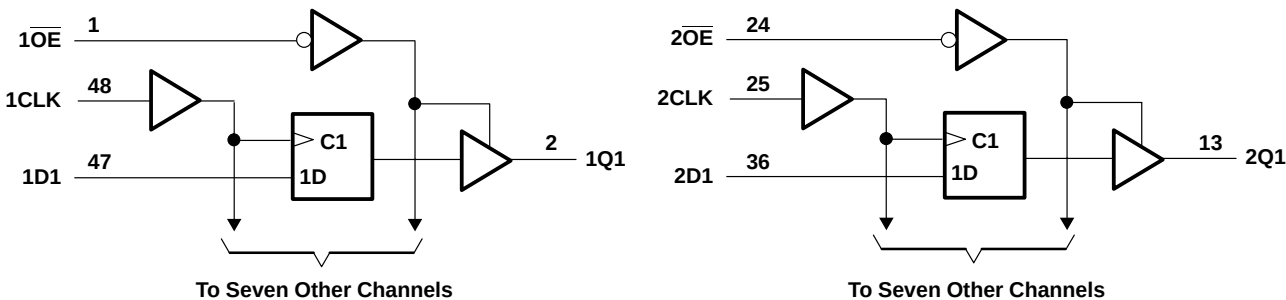
INPUTS			OUTPUT
$\overline{OE}$	CLK	D	Q
L	$\uparrow$	H	H
L	$\uparrow$	L	L
L	H or L	X	Q_0
H	X	X	Z

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



SN74ALVCH16374
16-BIT EDGE-TRIGGERED D-TYPE FLIP-FLOP
WITH 3-STATE OUTPUTS

SCES021D – JULY 1995 – REVISED FEBRUARY 1999

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	89°C/W
DL package	94°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate			10	ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



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WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP†	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V†	3.6 V	±500			
I _{OZ}	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	3.3 V	3			pF
	Data inputs		6			
C _O	Outputs	3.3 V	7			pF

† All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

‡ This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency	§		150		150		150		MHz
t _w	Pulse duration, CLK high or low	§		3.3		3.3		3.3		ns
t _{su}	Setup time, data before CLK↑	§		2.1		2.2		1.9		ns
t _h	Hold time, data after CLK↑	§		0.6		0.5		0.5		ns

§ This information was not available at the time of publication.



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WITH 3-STATE OUTPUTS

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	CLK	Q	†		1	5.3	4.9		1	4.2	ns
t _{en}	$\overline{OE}$	Q	†		1	6.2	5.9		1	4.8	ns
t _{dis}	$\overline{OE}$	Q	†		1	5.3	4.7		1.2	4.3	ns

† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 50 pF, f = 10 MHz	†	31	30	pF
		Outputs disabled		†	16	18	

† This information was not available at the time of publication.

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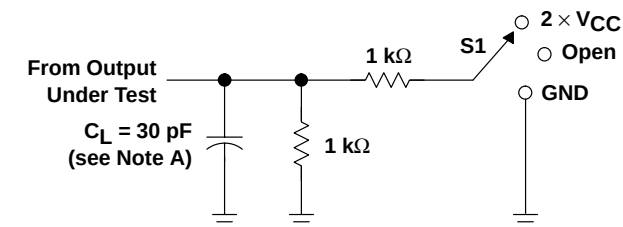
16-BIT EDGE-TRIGGERED D-TYPE FLIP-FLOP

WITH 3-STATE OUTPUTS

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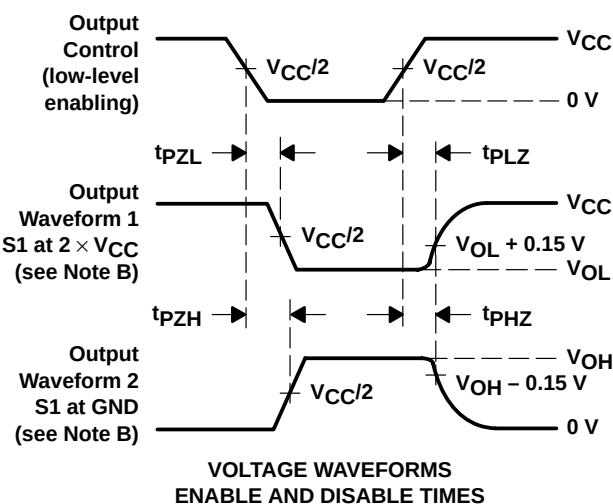
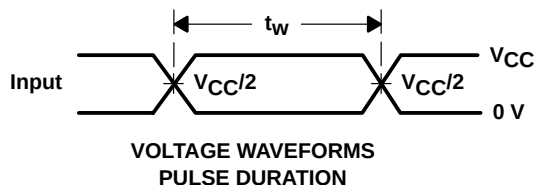
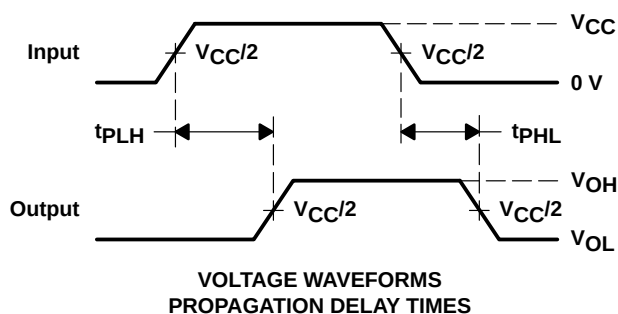
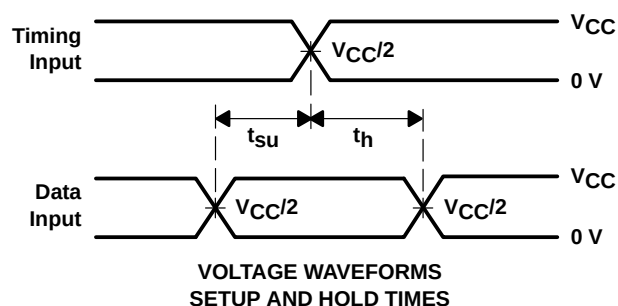
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PHL}	GND

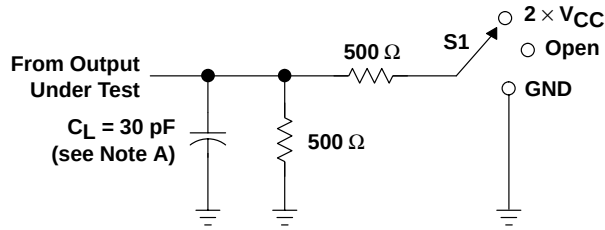


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

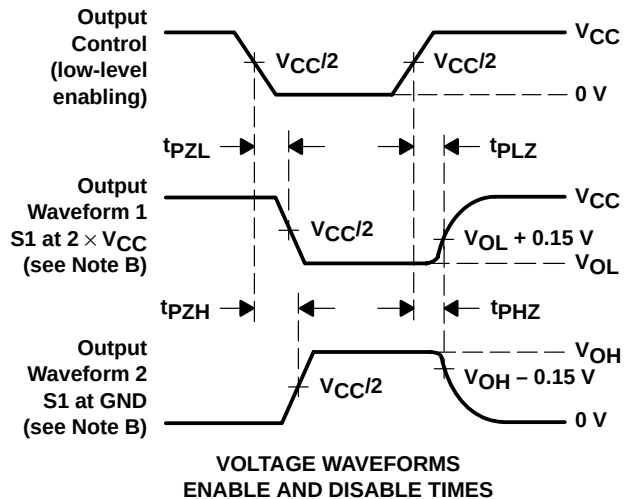
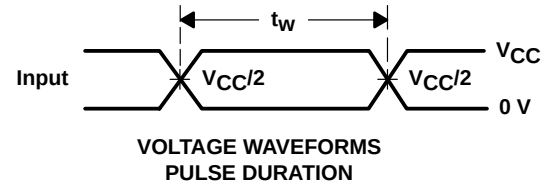
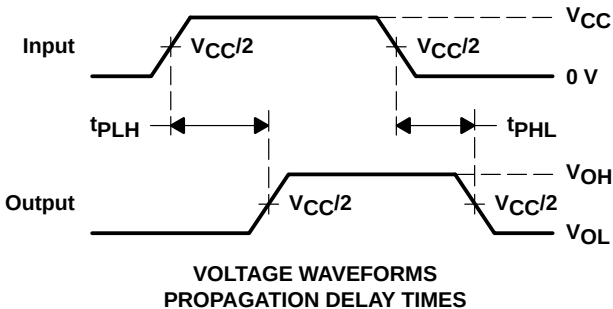
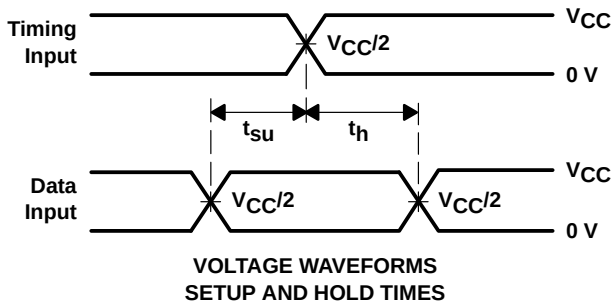
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	$2 \times V_{CC}$
t_{PHZ}/t_{PHZ}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

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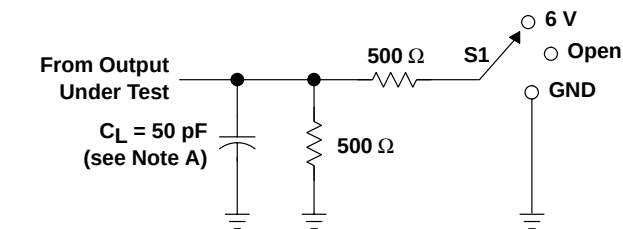
16-BIT EDGE-TRIGGERED D-TYPE FLIP-FLOP

WITH 3-STATE OUTPUTS

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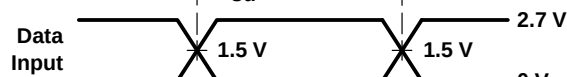
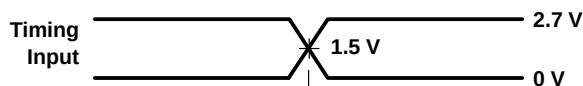
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$

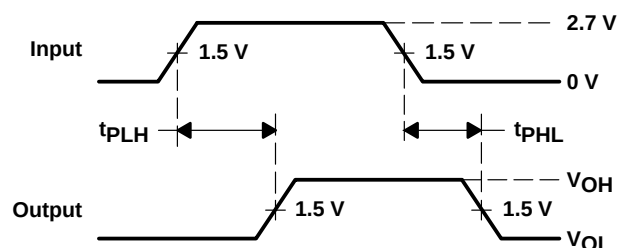


LOAD CIRCUIT

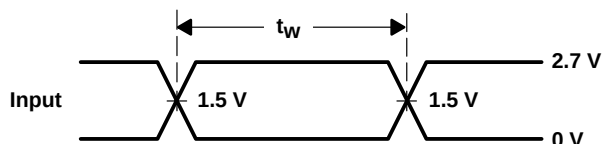
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



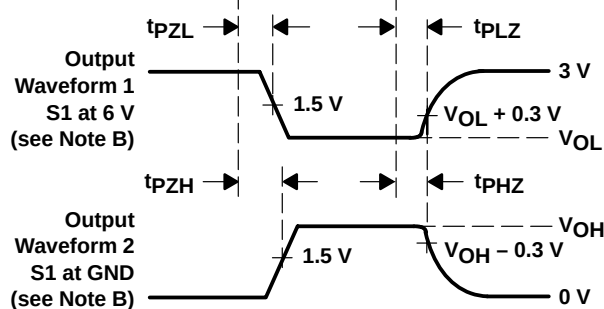
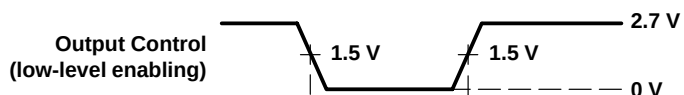
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16409

9-BIT, 4-PORT UNIVERSAL BUS EXCHANGER WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus+*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- *UBE*™ (Universal Bus Exchanger) Allows Synchronous Data Exchange
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 9-bit, 4-port universal bus exchanger is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16409 allows synchronous data exchange between four different buses. Data flow is controlled by the select ($\overline{SEL0}$ – $\overline{SEL4}$) inputs. A data-flow state is stored on the rising edge of the clock (CLK) input if the select-enable ($\overline{SELEN}$) input is low. Once a data-flow state has been established, data is stored in the flip-flop on the rising edge of CLK if $\overline{SELEN}$ is high.

The data-flow control logic is designed to allow glitch-free data transmission.

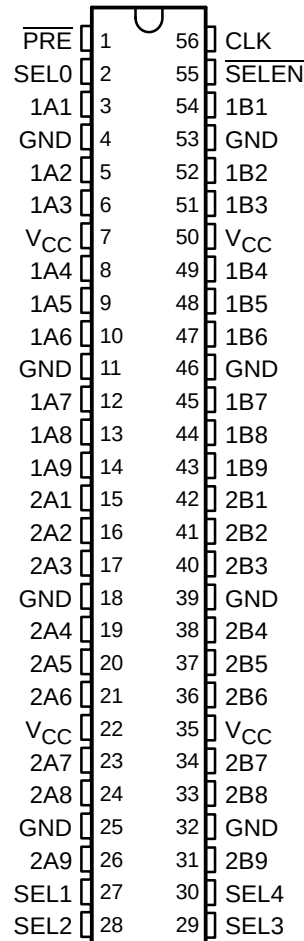
When preset ($\overline{PRE}$) transitions high, the outputs are disabled immediately, without waiting for a clock pulse. To leave the high-impedance state, both $\overline{PRE}$ and $\overline{SELEN}$ must be low and a clock pulse must be applied.

To ensure the high-impedance state during power up or power down, $\overline{PRE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16409 is characterized for operation from –40°C to 85°C.

DGG OR DL PACKAGE
(TOP VIEW)



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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SN74ALVCH16409
9-BIT, 4-PORT UNIVERSAL BUS EXCHANGER
WITH 3-STATE OUTPUTS

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Function Tables

INPUTS		OUTPUT RECEIVE PORT
CLK	SEND PORT	
X	X	B ₀ [†]
X	L	L
X	H	H
↑	L	L
↑	H	H
H	X	B ₀ [†]
L	X	B ₀ [†]

[†] Output level before the indicated steady-state input conditions were established

DATA-FLOW CONTROL

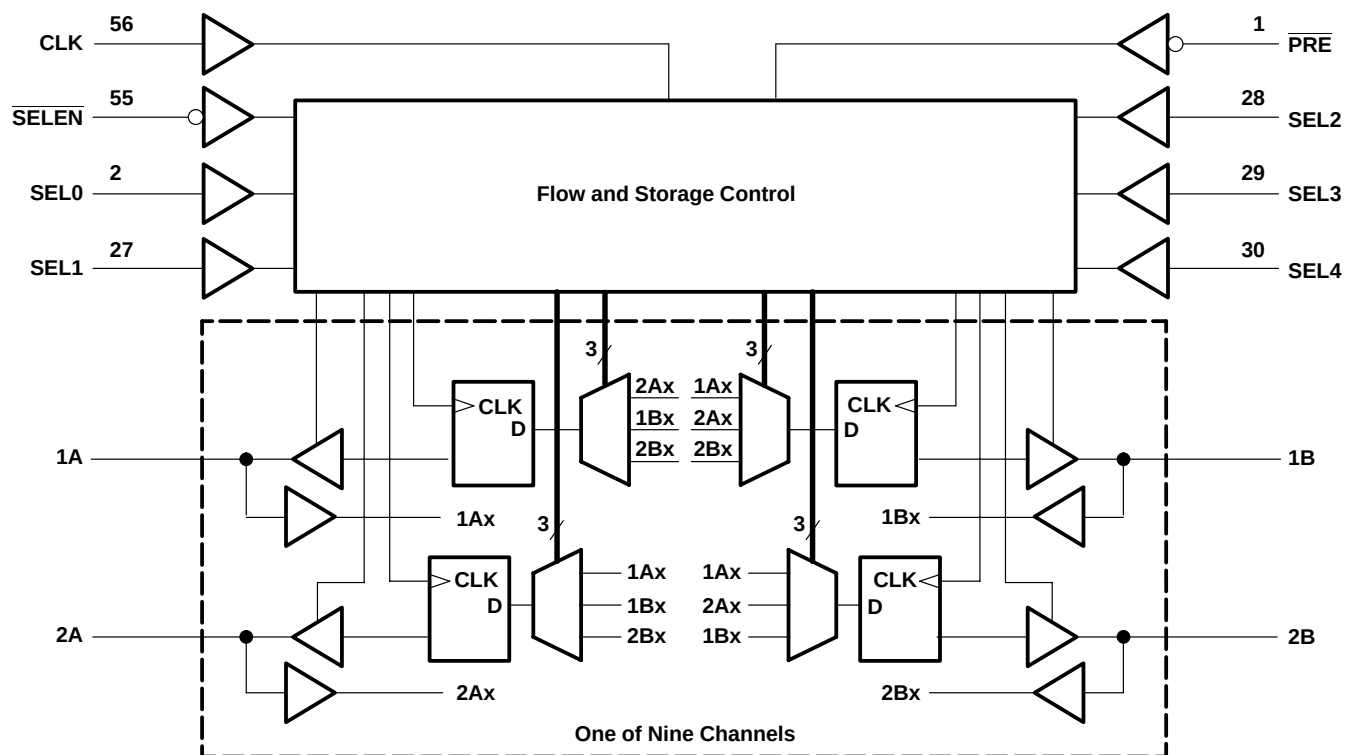
INPUTS								DATA FLOW
PRE	SELEN	CLK	SEL0	SEL1	SEL2	SEL3	SEL4	
H	X	X	X	X	X	X	X	All outputs disabled
L	H	↑	X	X	X	X	X	No change
L	L	↑	0	0	0	0	0	None, all I/Os off
L	L	↑	0	0	0	0	1	Not used
L	L	↑	0	0	0	1	0	Not used
L	L	↑	0	0	0	1	1	Not used
L	L	↑	0	0	1	0	0	Not used
L	L	↑	0	0	1	0	1	Not used
L	L	↑	0	0	1	1	0	Not used
L	L	↑	0	0	1	1	1	Not used
L	L	↑	0	1	0	0	0	2A to 1A and 1B to 2B
L	L	↑	0	1	0	0	1	2A to 1A
L	L	↑	0	1	0	1	0	2B to 1B
L	L	↑	0	1	0	1	1	2A to 1A and 2B to 1B
L	L	↑	0	1	1	0	0	1A to 2A and 1B to 2B
L	L	↑	0	1	1	0	1	1A to 2A
L	L	↑	0	1	1	1	0	1B to 2B
L	L	↑	0	1	1	1	1	1A to 2A and 2B to 1B
L	L	↑	1	0	0	0	0	1A to 1B and 2B to 2A
L	L	↑	1	0	0	0	1	1A to 1B
L	L	↑	1	0	0	1	0	2A to 2B
L	L	↑	1	0	0	1	1	1A to 1B and 2A to 2B
L	L	↑	1	0	1	0	0	1B to 1A and 2A to 2B
L	L	↑	1	0	1	0	1	1B to 1A
L	L	↑	1	0	1	1	0	2B to 2A
L	L	↑	1	0	1	1	1	1B to 1A and 2B to 2A
L	L	↑	1	1	0	0	0	2B to 1A and 2A to 1B
L	L	↑	1	1	0	0	1	1B to 2A
L	L	↑	1	1	0	1	0	2B to 1A
L	L	↑	1	1	0	1	1	2B to 1A and 1B to 2A
L	L	↑	1	1	1	0	0	1A to 2B and 1B to 2A
L	L	↑	1	1	1	0	1	1A to 2B
L	L	↑	1	1	1	1	0	2A to 1B
L	L	↑	1	1	1	1	1	1A to 2B and 2A to 1B



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9-BIT, 4-PORT UNIVERSAL BUS EXCHANGER
WITH 3-STATE OUTPUTS

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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{Stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–4	mA
		$V_{CC} = 2.3 \text{ V}$	–12	
		$V_{CC} = 2.7 \text{ V}$	–12	
		$V_{CC} = 3 \text{ V}$	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	4	mA
		$V_{CC} = 2.3 \text{ V}$	12	
		$V_{CC} = 2.7 \text{ V}$	12	
		$V_{CC} = 3 \text{ V}$	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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9-BIT, 4-PORT UNIVERSAL BUS EXCHANGER
WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
		I _{OL} = 12 mA	2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ} [§]		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	4			pF
C _{iO}	A or B ports	V _O = V _{CC} or GND	3.3 V	8			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.



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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency		†		120		120		120		MHz
t _w	Pulse duration, CLK high or low		†		4.2		4.2		3		ns
t _{su}	Setup time	A or B before CLK↑	†		1.9		1.9		1.4		ns
		SEL before CLK↑	†		5.1		4.2		3.5		
		$\overline{\text{SELEN}}$ before CLK↑	†		2.5		2.5		1.8		
		$\overline{\text{PRE}}$ before CLK↑	†		1		1		0.7		
t _h	Hold time	A or B after CLK↑	†		0.8		0.8		1		ns
		SEL after CLK↑	†		0		0		0		
		$\overline{\text{SELEN}}$ after CLK↑	†		0.5		0.5		0.8		

† This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 1.8\text{ V}$		$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f_{max}			†		120		120		120		MHz
t_{pd}	CLK	A or B	†		1.5	6	5.7		1.5	5.1	ns
t_{en}	CLK	A or B	†		2.4	6.9	6.3		2	5.7	ns
t_{dis}	CLK	A or B	†		2.3	7.1	6		2	5.7	ns
	PRE		†		2.8	7.5	6.5		2.5	6.1	

† This information was not available at the time of publication.

operating characteristics, $T_A = 25^\circ\text{C}$

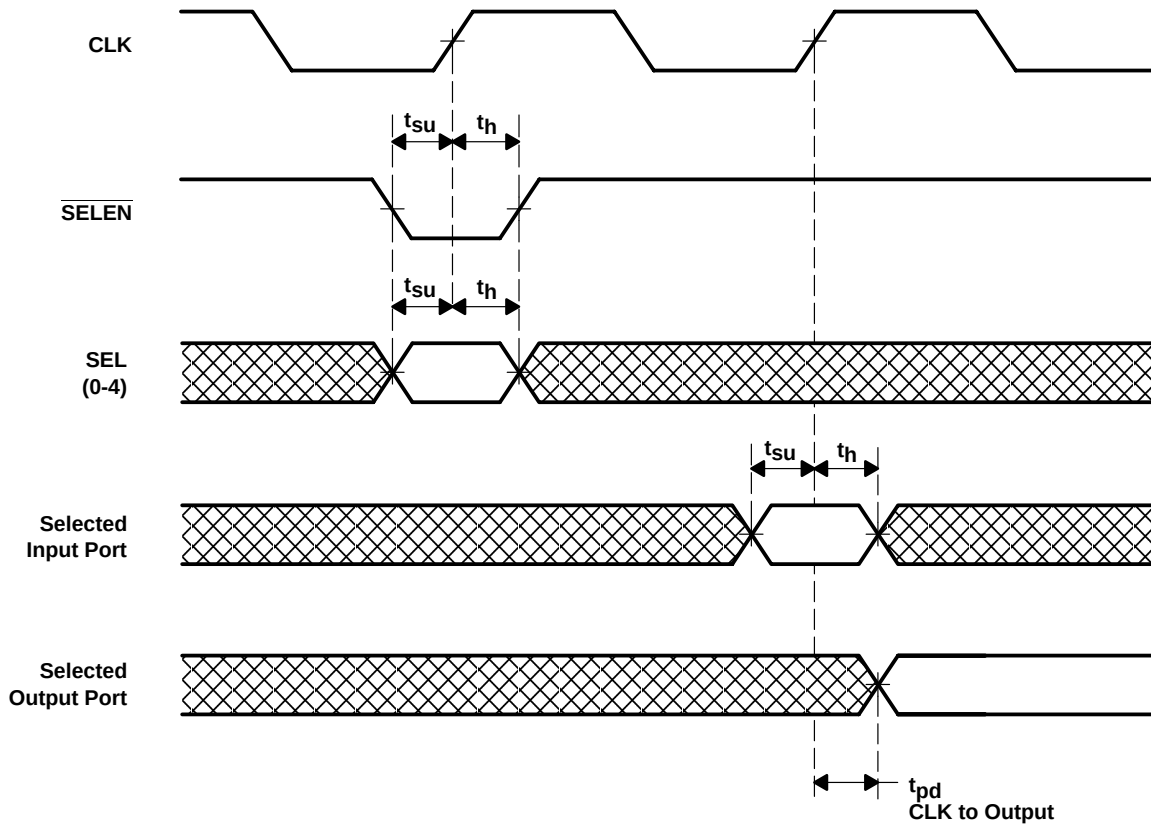
PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd}	Power dissipation capacitance per exchanger	All outputs enabled	†	60	60	pF
		All outputs disabled	†	60	60	

† This information was not available at the time of publication.

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timing diagram



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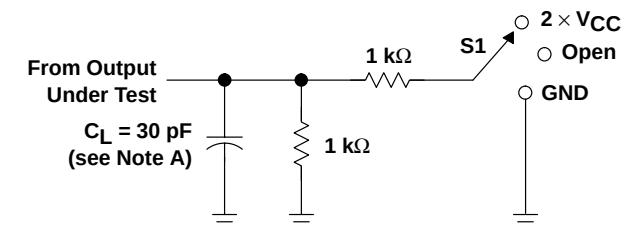
9-BIT, 4-PORT UNIVERSAL BUS EXCHANGER

WITH 3-STATE OUTPUTS

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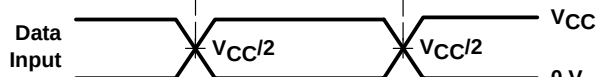
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$

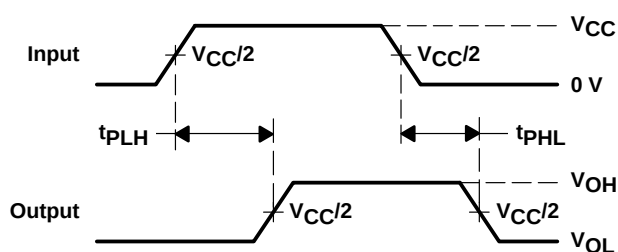


LOAD CIRCUIT

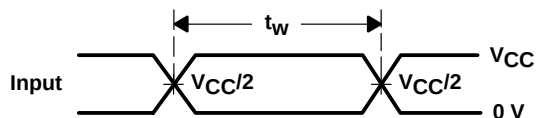
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PHZ}	GND



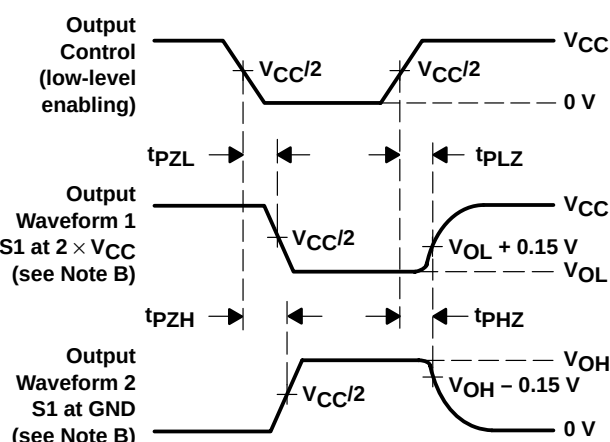
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



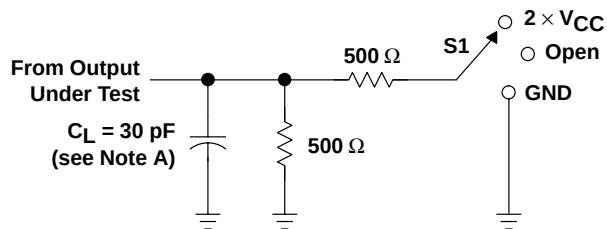
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

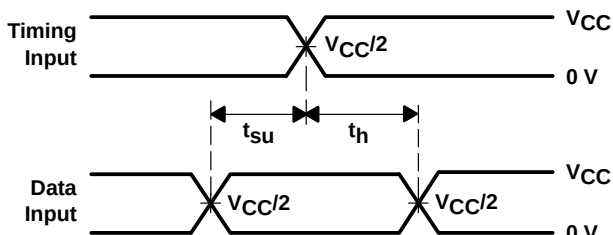
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

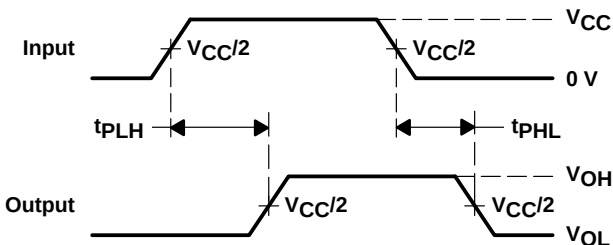


LOAD CIRCUIT

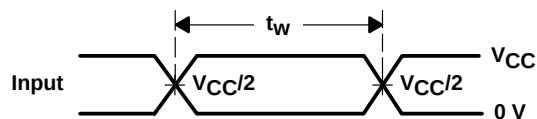
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



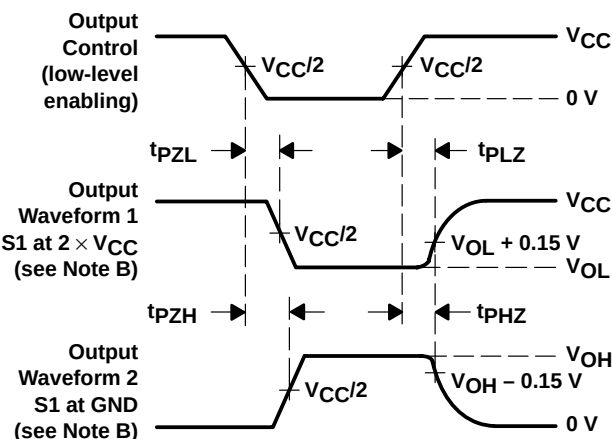
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

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 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

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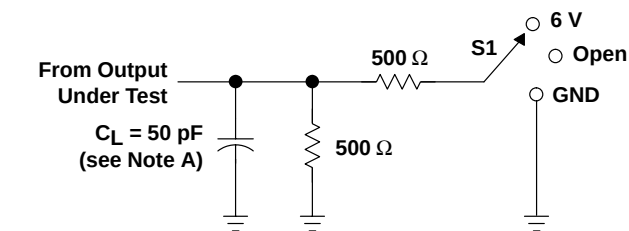
9-BIT, 4-PORT UNIVERSAL BUS EXCHANGER

WITH 3-STATE OUTPUTS

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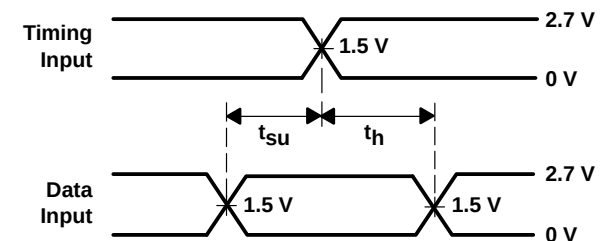
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$

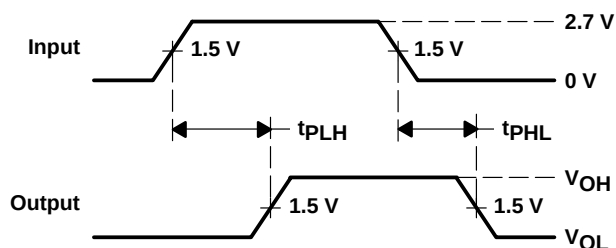


LOAD CIRCUIT

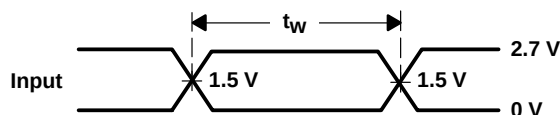
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



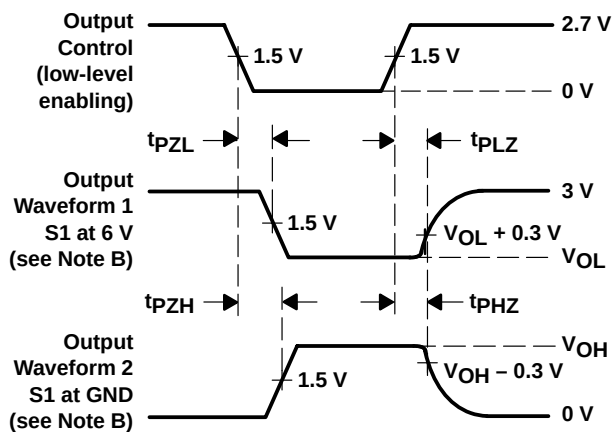
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16500

18-BIT UNIVERSAL BUS TRANSCEIVER WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- *UBT™* (Universal Bus Transceiver) Combines D-Type Latches and D-Type Flip-Flops for Operation in Transparent, Latched, or Clocked Mode
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 18-bit universal bus transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

Data flow in each direction is controlled by output-enable ($\overline{OEAB}$ and $\overline{OEBA}$), latch-enable ($\overline{LEAB}$ and $\overline{LEBA}$), and clock ($\overline{CLKAB}$ and $\overline{CLKBA}$) inputs. For A-to-B data flow, the device operates in the transparent mode when $\overline{LEAB}$ is high. When $\overline{LEAB}$ is low, the A data is latched if $\overline{CLKAB}$ is held at a high or low logic level. If $\overline{LEAB}$ is low, the A data is stored in the latch/flip-flop on the high-to-low transition of $\overline{CLKAB}$. Output-enable $\overline{OEAB}$ is active high. When $\overline{OEAB}$ is high, the B-port outputs are active. When $\overline{OEAB}$ is low, the B-port outputs are in the high-impedance state.

Data flow for B to A is similar to that of A to B, but uses $\overline{OEBA}$, $\overline{LEBA}$, and $\overline{CLKBA}$. The output enables are complementary ($\overline{OEAB}$ is active high, and $\overline{OEBA}$ is active low).

To ensure the high-impedance state during power up or power down, $\overline{OEBA}$ should be tied to V_{CC} through a pullup resistor and $\overline{OEAB}$ should be tied to GND through a pulldown resistor; the minimum value of the resistor is determined by the current-sinking/current-sourcing capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16500 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)

OEAB	1	56	GND
LEAB	2	55	$\overline{CLKAB}$
A1	3	54	B1
GND	4	53	GND
A2	5	52	B2
A3	6	51	B3
V_{CC}	7	50	V_{CC}
A4	8	49	B4
A5	9	48	B5
A6	10	47	B6
GND	11	46	GND
A7	12	45	B7
A8	13	44	B8
A9	14	43	B9
A10	15	42	B10
A11	16	41	B11
A12	17	40	B12
GND	18	39	GND
A13	19	38	B13
A14	20	37	B14
A15	21	36	B15
V_{CC}	22	35	V_{CC}
A16	23	34	B16
A17	24	33	B17
GND	25	32	GND
A18	26	31	B18
$\overline{OEBA}$	27	30	$\overline{CLKBA}$
$\overline{LEBA}$	28	29	GND

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WITH 3-STATE OUTPUTS

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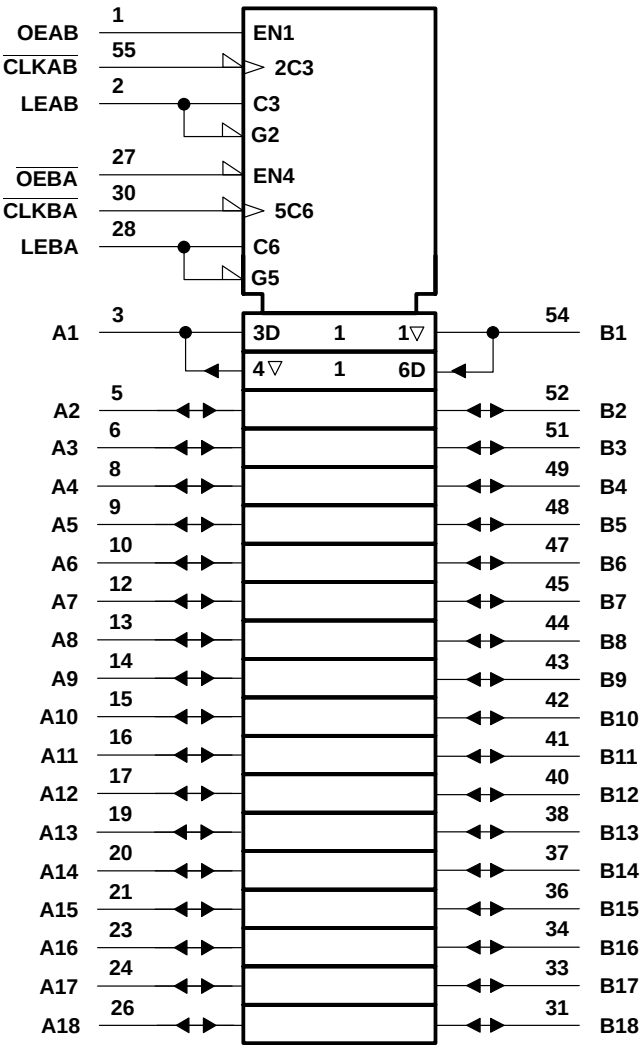
FUNCTION TABLE†

INPUTS				OUTPUT B
OEAB	LEAB	CLKAB	A	
L	X	X	X	Z
H	H	X	L	L
H	H	X	H	H
H	L	O	L	L
H	L	↓	H	H
H	L	L or H	X	B ₀ ‡

† A-to-B data flow is shown; B-to-A flow is similar, but uses OEBA, LEBA, and CLKBA.

‡ Output level before the indicated steady-state input conditions were established

logic symbols§



§ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

The diagram illustrates the logic for a 17-channel receiver. On the left, eight input signals are listed: OEAB (1), CLKAB (55), LEAB (2), LEBA (28), CLKBA (30), OEBA (27), and A1 (3). Each of these signals passes through an inverter. The outputs of these inverters are connected to various points in the circuit. Two 1D C1 blocks are present. The first 1D C1 block has its 1D input connected to A1 (via a buffer), its C1 input connected to the output of the OEBA inverter, and its CLK input connected to the output of the CLKBA inverter. The second 1D C1 block has its 1D input connected to the output of the OEAB inverter, its C1 input connected to the output of the OEBA inverter, and its CLK input connected to the output of the CLKBA inverter. The outputs of these blocks are connected to a series of inverters, which then lead to a final output signal B1 (54). A bracket at the bottom indicates that the circuit is part of a larger system with 17 other channels.

Supply voltage range, V_{CC}		-0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)		-0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)		-0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)		-0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)		-50 mA
Output clamp current, I_{OK} ($V_O < 0$)		-50 mA
Continuous output current, I_O		± 50 mA
Continuous current through each V_{CC} or GND		± 100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package		81°C/W
DL package		74°C/W
Storage temperature range, T_{stg}		-65°C to 150°C

NOTES:

1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–4	mA
		$V_{CC} = 2.3 \text{ V}$	–12	
		$V_{CC} = 2.7 \text{ V}$	–12	
		$V_{CC} = 3 \text{ V}$	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	4	mA
		$V_{CC} = 2.3 \text{ V}$	12	
		$V_{CC} = 2.7 \text{ V}$	12	
		$V_{CC} = 3 \text{ V}$	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
		I _{OL} = 12 mA	2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ} [§]		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	4			pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V	8			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.



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WITH 3-STATE OUTPUTS

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT	
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
f _{clock}	Clock frequency		†		150		150		150		MHz	
t _w	Pulse duration	LE high	†		3.3		3.3		3.3		ns	
		CLK high or low		†		3.3		3.3				
t _{su}	Setup time	Data before CLK↓		†		1.7		1.4		1.3		ns
		Data before LE↓	CLK high	†		1.1		1		1		
			CLK low	†		1.9		1.6		1.4		
t _h	Hold time	Data after CLK↓		†		1.7		1.6		1.3		ns
		Data after LE↓	CLK high	†		2		1.8		1.5		
			CLK low	†		1.6		1.5		1.2		

† This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	A or B	B or A	†		1 5.1		4.7		1 3.9		ns
	LEAB or LEBA	A or B	†		1 5.9		5.5		1 4.7		
	CLKAB or CLKBA		†		1 6.6		6.6		1.1 5.5		
t _{en}	OEAB	B	†		1 5.7		5.4		1 4.6		ns
t _{dis}	OEAB	B	†		1 6.1		5.7		1.5 5		ns
t _{en}	OEBA	A	†		1 6.2		6.2		1 5.2		ns
t _{dis}	OEBA	A	†		1 5.4		4.6		1 4.3		ns

† This information was not available at the time of publication.

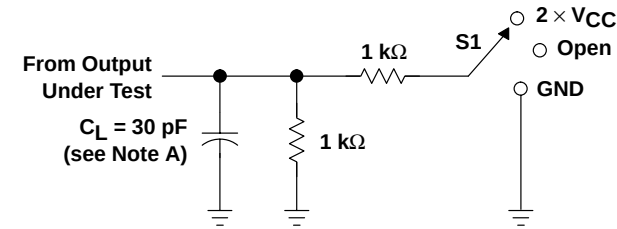
operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 50 pF, f = 10 MHz	†	40	51	pF
		Outputs disabled		†	6	6	

† This information was not available at the time of publication.

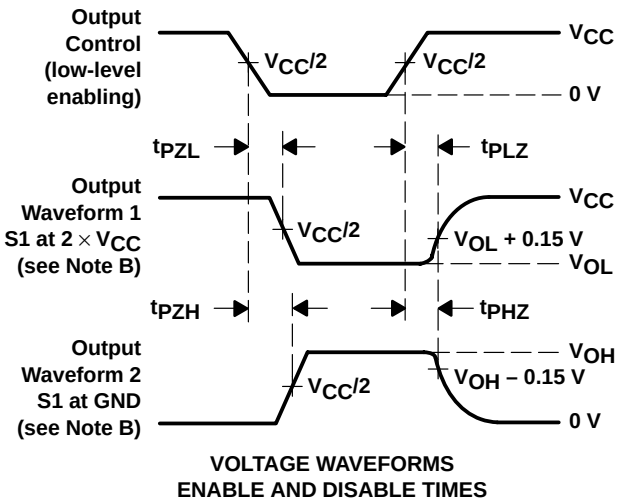
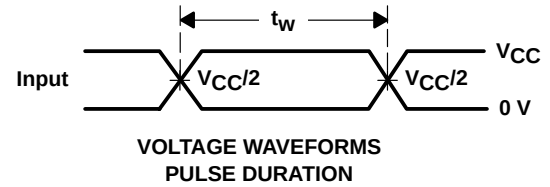
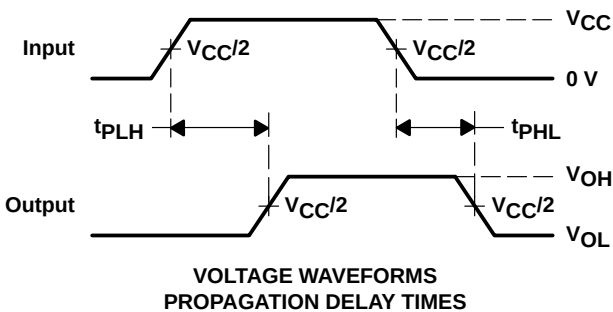
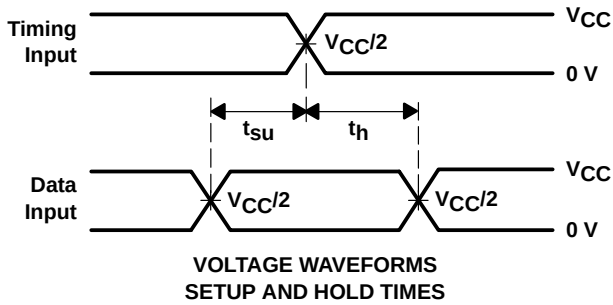


PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH16500

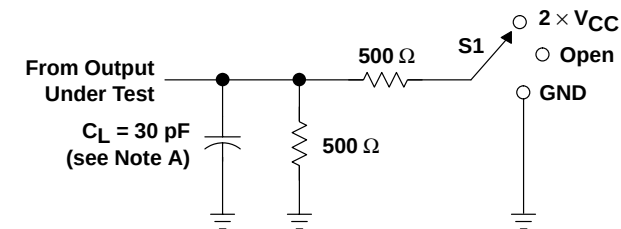
18-BIT UNIVERSAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

SCES023F – JULY 1995 – REVISED FEBRUARY 1999

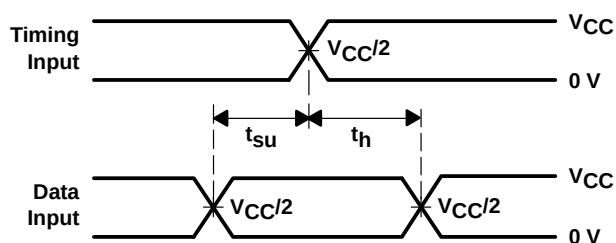
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

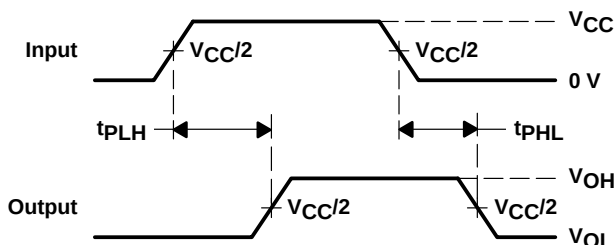


LOAD CIRCUIT

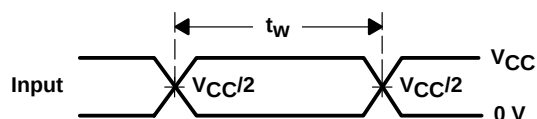
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



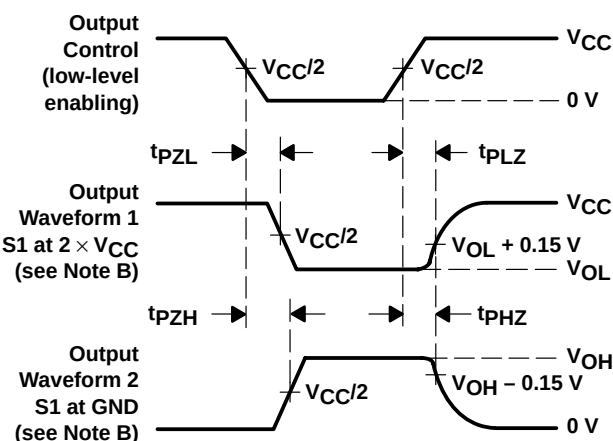
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



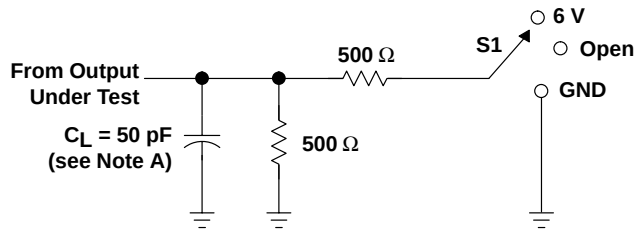
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

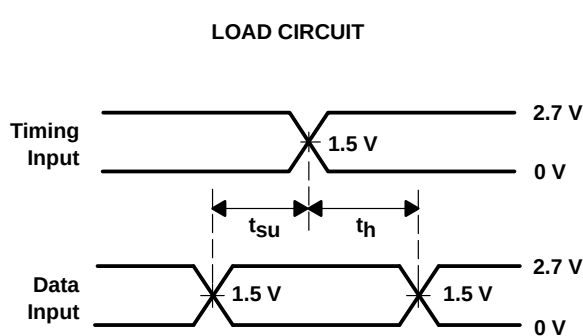
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

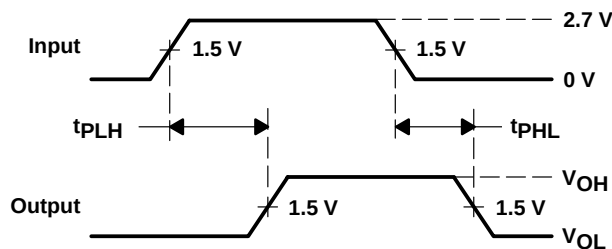


LOAD CIRCUIT

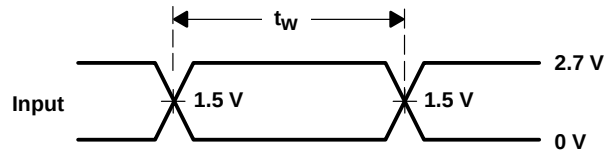
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



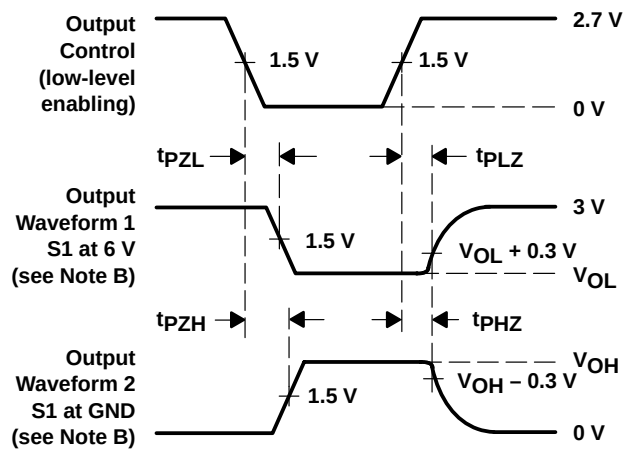
**VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES**



**VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES**



**VOLTAGE WAVEFORMS
PULSE DURATION**



**VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES**

- NOTES: A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
- D. The outputs are measured one at a time with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16501

18-BIT UNIVERSAL BUS TRANSCEIVER WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- *UBT™* (Universal Bus Transceiver) Combines D-Type Latches and D-Type Flip-Flops for Operation in Transparent, Latched, or Clocked Mode
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 18-bit universal bus transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

Data flow in each direction is controlled by output-enable ($\overline{OEAB}$ and $\overline{OEBA}$), latch-enable ($\overline{LEAB}$ and $\overline{LEBA}$), and clock ($\overline{CLKAB}$ and $\overline{CLKBA}$) inputs. For A-to-B data flow, the device operates in the transparent mode when $\overline{LEAB}$ is high. When $\overline{LEAB}$ is low, the A data is latched if $\overline{CLKAB}$ is held at a high or low logic level. If $\overline{LEAB}$ is low, the A data is stored in the latch/flip-flop on the low-to-high transition of $\overline{CLKAB}$. When $\overline{OEAB}$ is high, the outputs are active. When $\overline{OEAB}$ is low, the outputs are in the high-impedance state.

Data flow for B to A is similar to that of A to B, but uses $\overline{OEBA}$, $\overline{LEBA}$, and $\overline{CLKBA}$. The output enables are complementary ($\overline{OEAB}$ is active high and $\overline{OEBA}$ is active low).

To ensure the high-impedance state during power up or power down, $\overline{OEBA}$ should be tied to V_{CC} through a pullup resistor and $\overline{OEAB}$ should be tied to GND through a pulldown resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16501 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)

OEAB	1	56	GND
LEAB	2	55	CLKAB
A1	3	54	B1
GND	4	53	GND
A2	5	52	B2
A3	6	51	B3
V _{CC}	7	50	V _{CC}
A4	8	49	B4
A5	9	48	B5
A6	10	47	B6
GND	11	46	GND
A7	12	45	B7
A8	13	44	B8
A9	14	43	B9
A10	15	42	B10
A11	16	41	B11
A12	17	40	B12
GND	18	39	GND
A13	19	38	B13
A14	20	37	B14
A15	21	36	B15
V _{CC}	22	35	V _{CC}
A16	23	34	B16
A17	24	33	B17
GND	25	32	GND
A18	26	31	B18
$\overline{OEBA}$	27	30	CLKBA
$\overline{LEBA}$	28	29	GND

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WITH 3-STATE OUTPUTS

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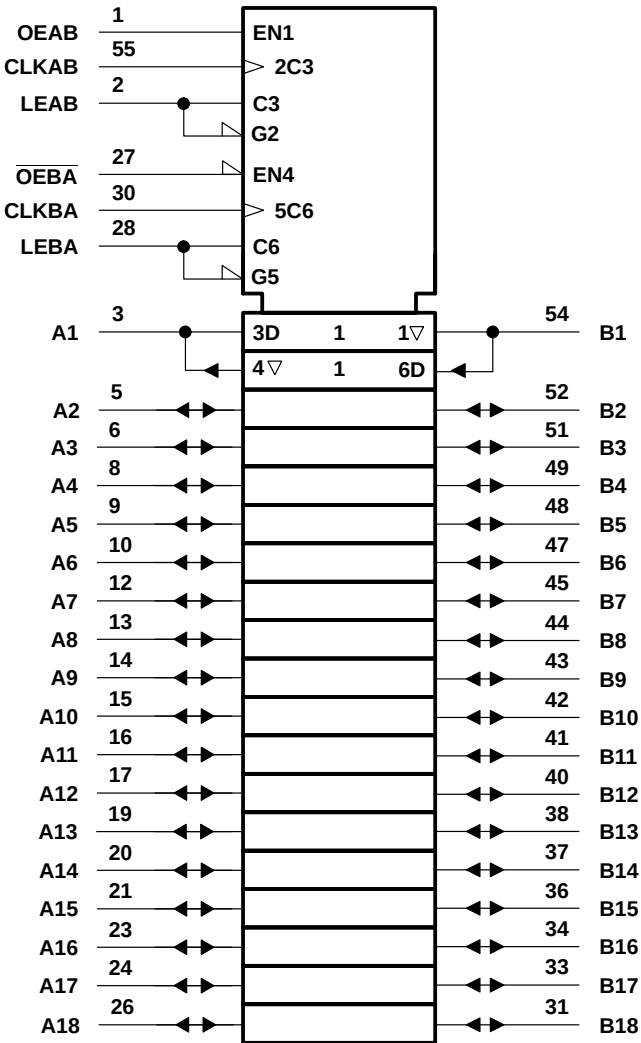
FUNCTION TABLE†

INPUTS				OUTPUT B
OEAB	LEAB	CLKAB	A	
L	X	X	X	Z
H	H	X	L	L
H	H	X	H	H
H	L	↑	L	L
H	L	↑	H	H
H	L	L or H	X	B ₀ ‡

† A-to-B data flow is shown: B-to-A flow is similar, but uses OEBA, LEBA, and CLKBA.

‡ Output level before the indicated steady-state input conditions were established, provided that CLKAB is high before LEAB goes low

logic symbols§

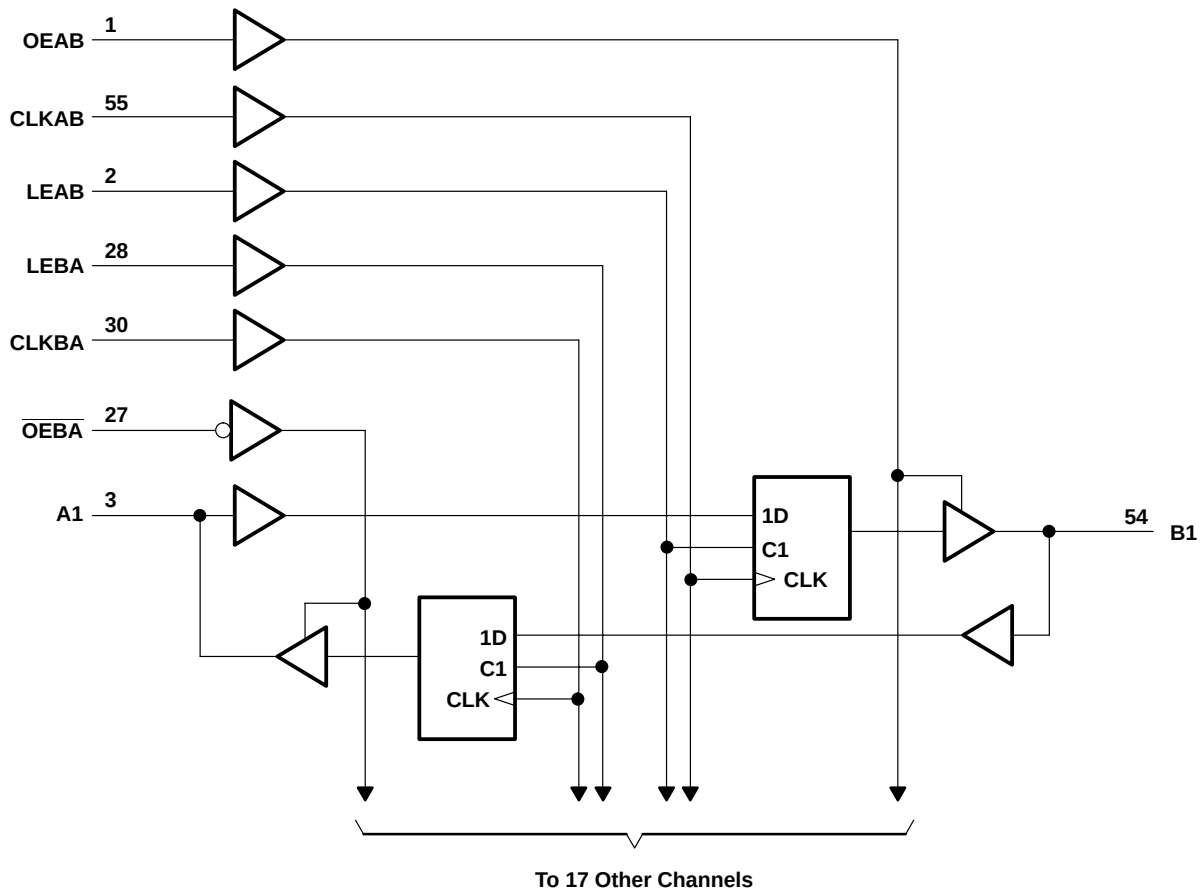


§ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.



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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–4	mA
		$V_{CC} = 2.3 \text{ V}$	–12	
		$V_{CC} = 2.7 \text{ V}$	–12	
		$V_{CC} = 3 \text{ V}$	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	4	mA
		$V_{CC} = 2.3 \text{ V}$	12	
		$V_{CC} = 2.7 \text{ V}$	12	
		$V_{CC} = 3 \text{ V}$	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ} [§]	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V		4	pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V		8	pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT	
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
f _{clock}	Clock frequency		¶		150		150		150		MHz	
t _w	Pulse duration	LE high		¶		3.3		3.3		3.3		ns
		CLK high or low		¶		3.3		3.3		3.3		
t _{su}	Setup time	Data before CLK↑		¶		2.2		2.1		1.7		ns
		Data before LE↓	CLK high	¶		1.9		1.6		1.5		
			CLK low	¶		1.3		1.1		1		
t _h	Hold time	Data after CLK↑		¶		0.6		0.6		0.7		ns
		Data after LE↓	CLK high or low	¶		1.4		1.7		1.4		

¶ This information was not available at the time of publication.



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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	A or B	B or A		†	1	4.8		4.5	1	3.9	ns
	LE	A or B		†	1.1	5.7		5.3	1.3	4.6	
	CLK			†	1.2	6.1		5.6	1.4	4.9	
t _{en}	OEAB	B		†	1	5.8		5.3	1	4.6	ns
t _{dis}	OEAB	B		†	1.5	6.2		5.7	1.4	5	ns
t _{en}	$\overline{\text{OEBA}}$	A		†	1.3	6.3		6	1.1	5	ns
t _{dis}	$\overline{\text{OEBA}}$	A		†	1.3	5.3		4.6	1.3	4.2	ns

† This information was not available at the time of publication.

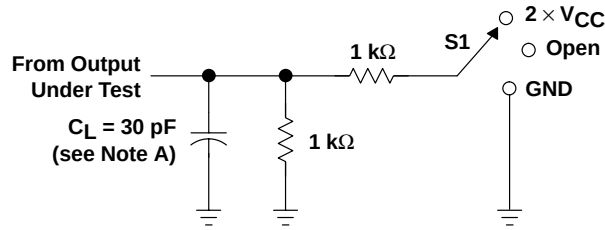
operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd} Power dissipation capacitance	Outputs enabled	C _L = 50 pF, f = 10 MHz		†	44	54	pF
	Outputs disabled			†	6	6	

† This information was not available at the time of publication.

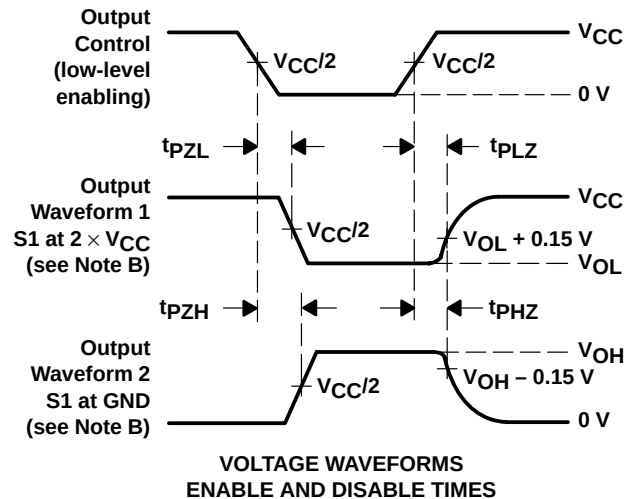
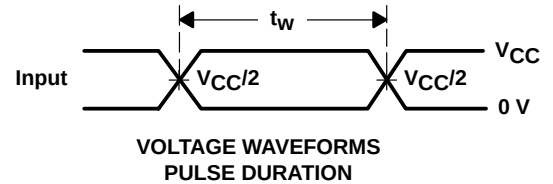
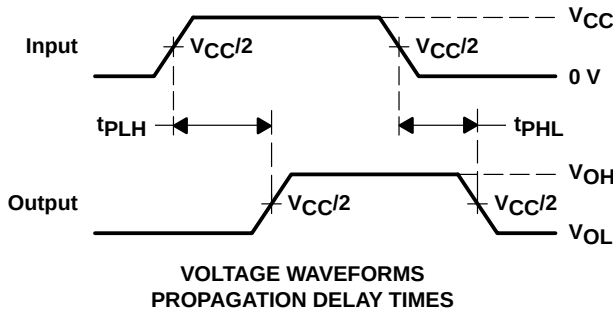
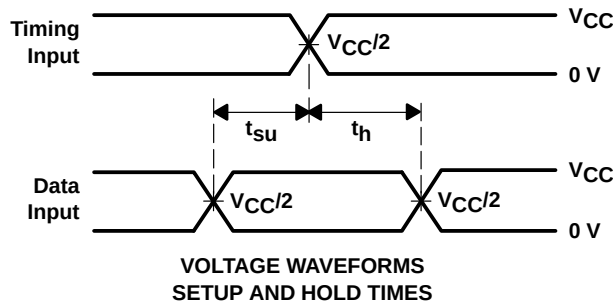
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH16501

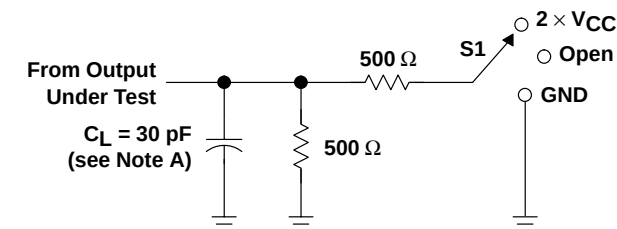
18-BIT UNIVERSAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

SCES024C – JULY 1995 – REVISED FEBRUARY 1999

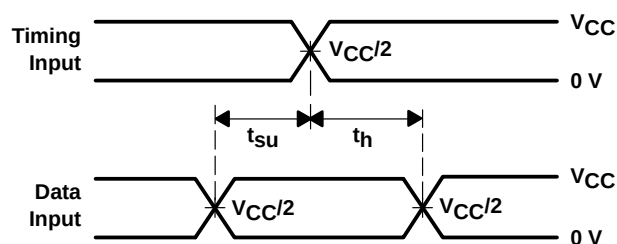
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

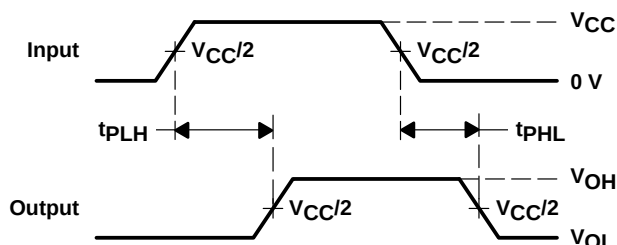


LOAD CIRCUIT

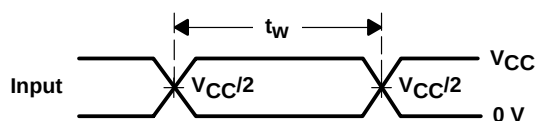
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



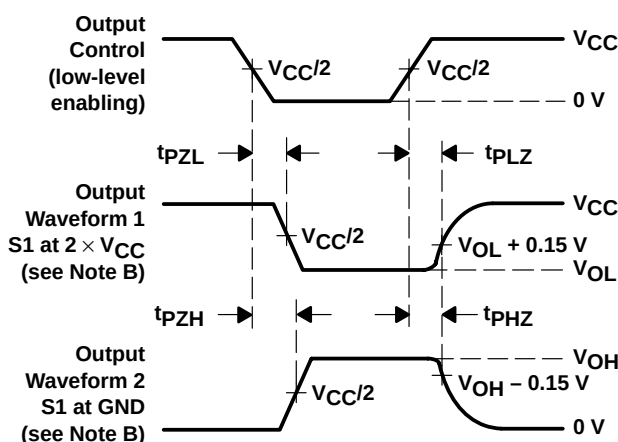
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



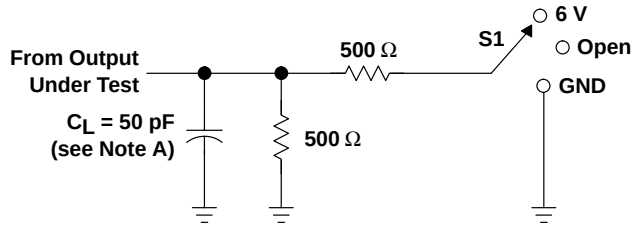
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

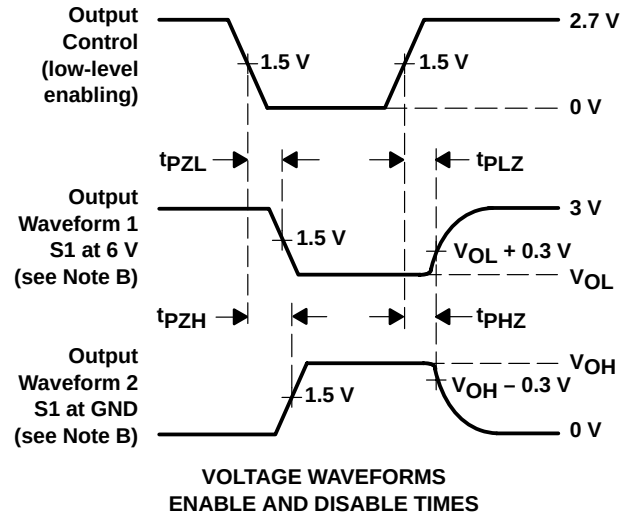
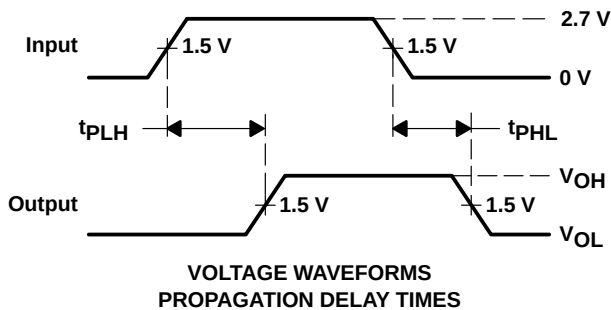
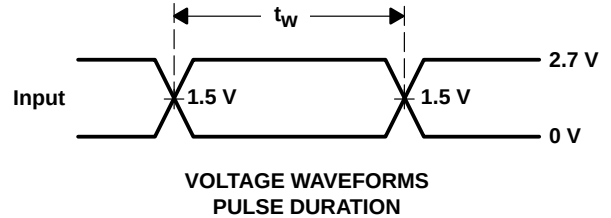
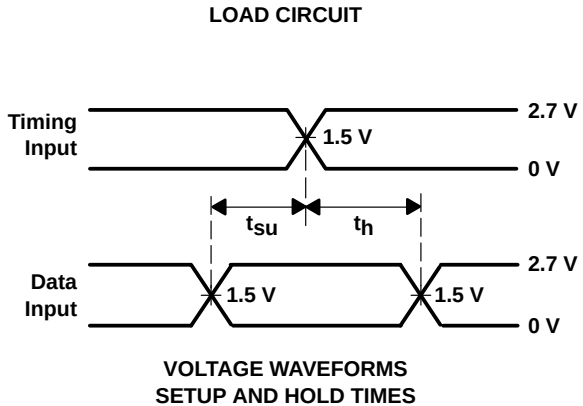
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V}$ AND $3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
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 - t_{PLZ} and t_{PHZ} are the same as t_{dLZ} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16524

18-BIT REGISTERED BUS TRANSCEIVER WITH 3-STATE OUTPUTS

SCES080C – JULY 1996 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 18-bit universal bus transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

Data flow in each direction is controlled by output-enable ($\overline{OEAB}$ and $\overline{OEBA}$) and clock-enable ($\overline{CLKENBA}$) inputs. For the A-to-B data flow, the data flows through a single buffer. The B-to-A data can flow through a four-stage pipeline register path, or through a single register path, depending on the state of the select ($\overline{SEL}$) input.

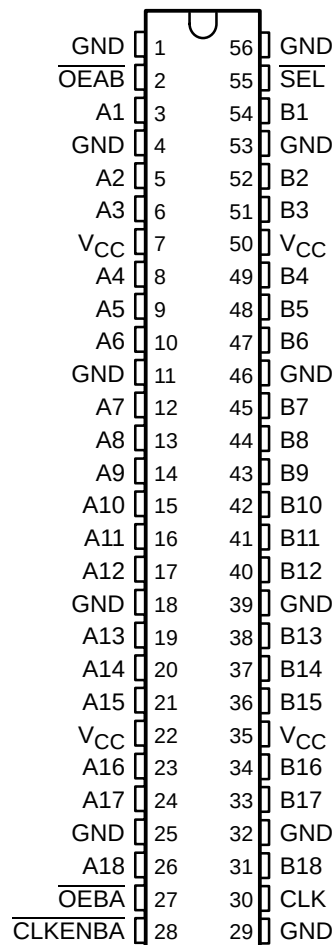
Data is stored in the internal registers on the low-to-high transition of the clock (CLK) input, provided that the appropriate $\overline{CLKENBA}$ input is low. The B-to-A data transfer is synchronized with CLK.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16524 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)



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SN74ALVCH16524

18-BIT REGISTERED BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

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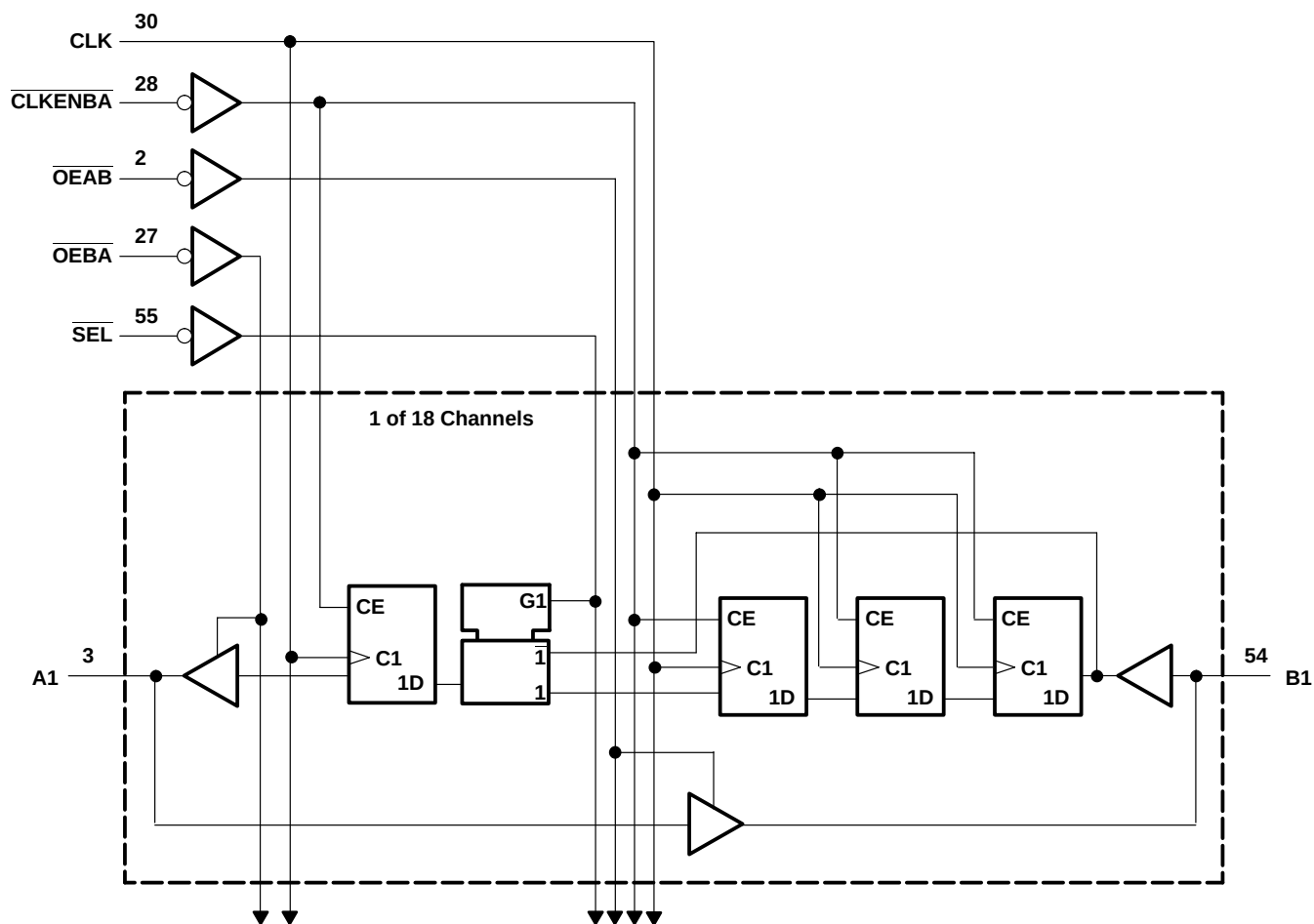
FUNCTION TABLE
B-TO-A STORAGE ($\overline{OEBA} = L$)

INPUTS				OUTPUT A
CLKENBA	CLK	$\overline{SEL}$	B	
H	X	X	X	$A_0^\dagger$
L	$\uparrow$	H	L	L
L	$\uparrow$	H	H	H
L	$\uparrow$	L	L	$L^\ddagger$
L	$\uparrow$	L	H	$H^\ddagger$

† Output level before the indicated steady-state input conditions were established

‡ Four positive CLK edges are needed to propagate data from B to A when $\overline{SEL}$ is low.

logic diagram (positive logic)



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18-BIT REGISTERED BUS TRANSCEIVER WITH 3-STATE OUTPUTS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = −100 μA	1.65 V to 3.6 V	V _{CC} −0.2			V
		I _{OH} = −4 mA	1.65 V	1.2			
		I _{OH} = −6 mA	2.3 V	2			
	I _{OH} = −12 mA		2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = −24 mA	3 V	2			
V _{OL}		I _{OL} = 100 μA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA		2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V	±5			μA
I _I (hold)		V _I = 0.58 V	1.65 V	25			μA
		V _I = 1.07 V	1.65 V	−25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	−45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	−75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ} [§]		V _O = V _{CC} or GND	3.6 V	±10			μA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			μA
ΔI _{CC}		One input at V _{CC} − 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			μA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3			pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V	7			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT		
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX			
f _{clock}	Clock frequency	¶		120		125		150		MHz		
t _w	Pulse duration, CLK high or low	¶		3.2		3.2		3		ns		
t _{su}	Setup time	B data before CLK↑		¶		1.5		1.2		1.1		ns
		SEL before CLK↑		¶		2.7		2.4		2.1		
		CLKENBA before CLK↑		¶		2.7		2.6		2		
t _h	Hold time	B data after CLK↑		¶		1		0.6		1.2		ns
		SEL after CLK↑		¶		0.5		0.2		0.8		
		CLKENBA after CLK↑		¶		0.1		0.1		0.3		

¶ This information was not available at the time of publication.



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18-BIT REGISTERED BUS TRANSCEIVER
WITH 3-STATE OUTPUTS

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		120		125		150		MHz
t _{pd}	A	B	†		1	3.9	3.8		1	3.2	ns
	CLK	A	†		1	6.1	6.2		1	5.2	
t _{en}	OEAB or OEBA	A or B	†		1	6.1	6.1		1	5.1	ns
t _{dis}	OEAB or OEBA	A or B	†		1	6.3	5.4		1	4.9	ns

† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 50 pF, f = 10 MHz	†	160	160	pF
		Outputs disabled		†	160	160	

† This information was not available at the time of publication.

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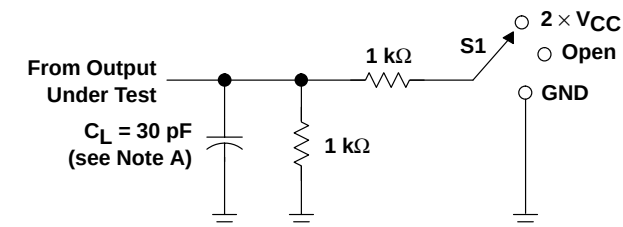
18-BIT REGISTERED BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

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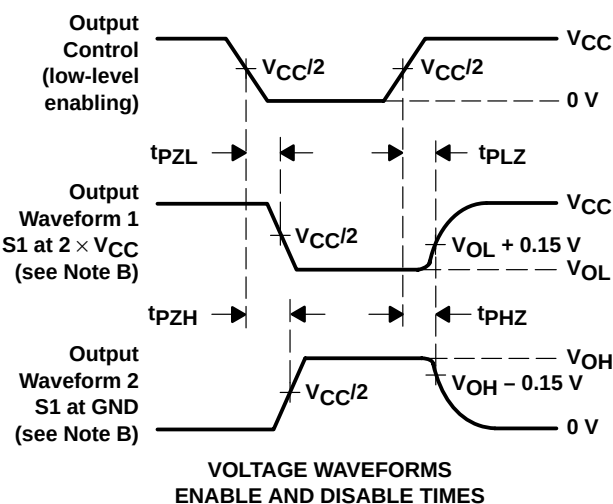
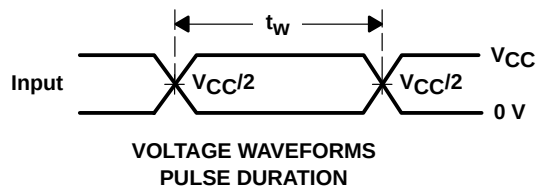
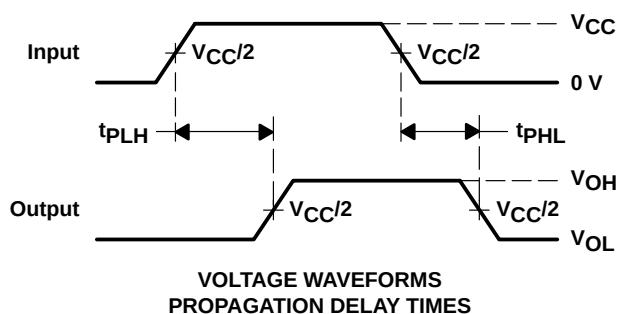
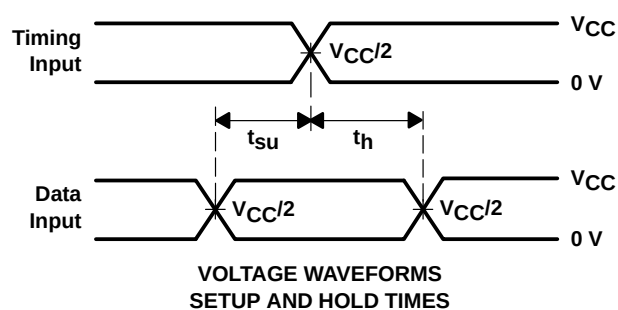
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PHL}	GND

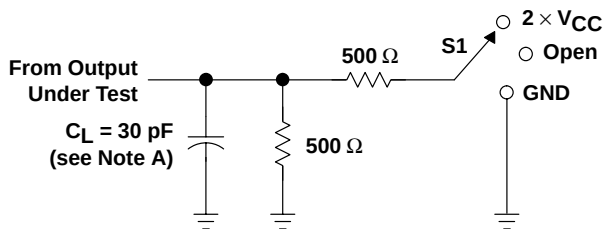


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
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 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

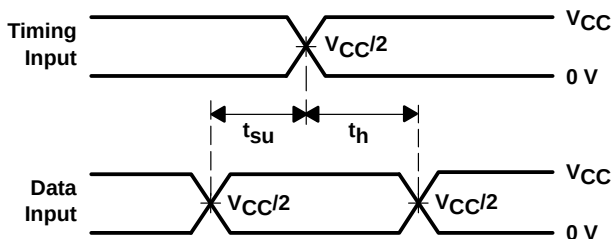
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$$

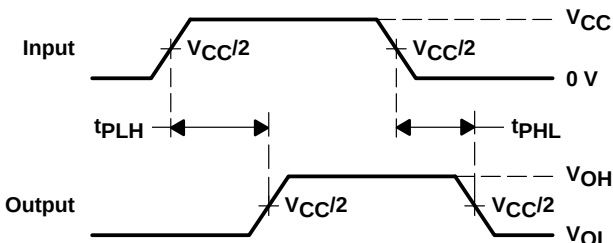


LOAD CIRCUIT

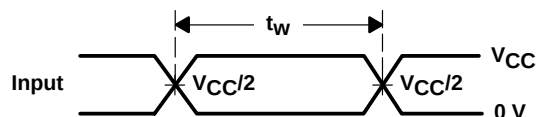
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	$2 \times V_{CC}$
t_{PHZ}/t_{PHZ}	GND



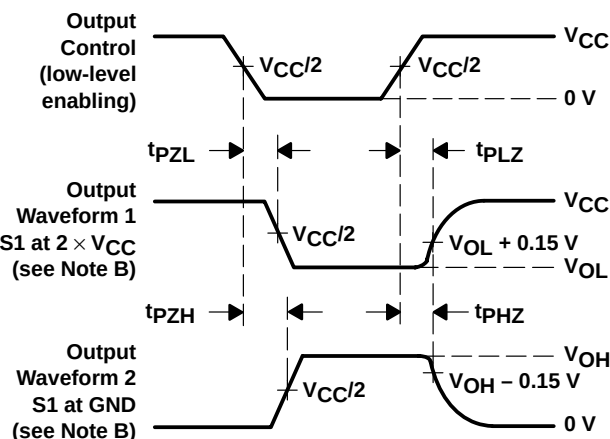
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

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Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH16524

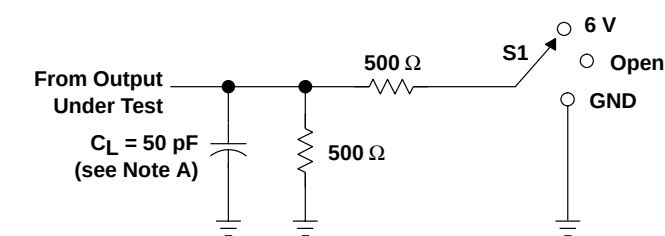
18-BIT REGISTERED BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

SCES080C – JULY 1996 – REVISED FEBRUARY 1999

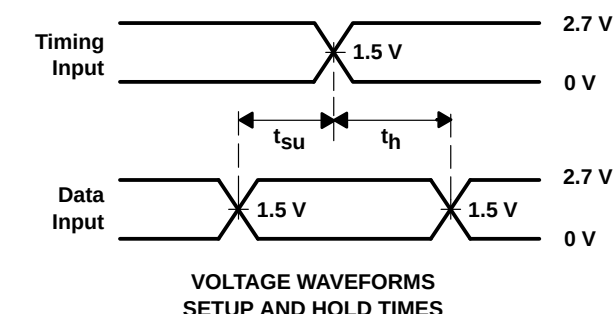
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$

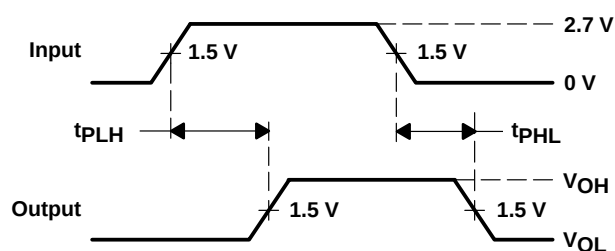


LOAD CIRCUIT

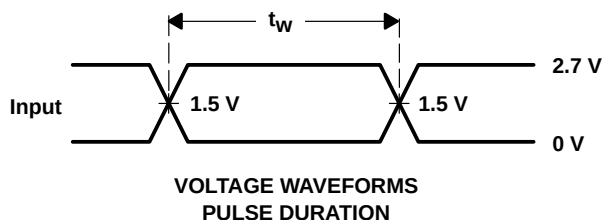
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



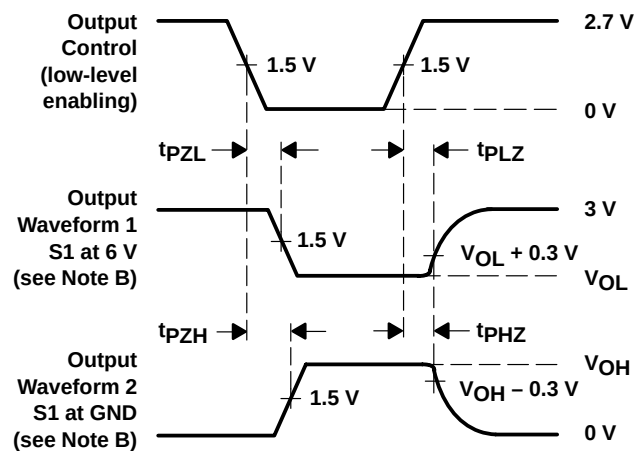
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

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 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
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 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16525

18-BIT REGISTERED BUS TRANSCEIVER WITH 3-STATE OUTPUTS

SCES059C – NOVEMBER 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Option Includes Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 18-bit universal bus transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

Data flow in each direction is controlled by output-enable ($\overline{OEAB}$ and $\overline{OEBA}$) and clock-enable ($\overline{CLKENAB}$ and $\overline{CLKENBA}$) inputs. For the A-to-B data flow, the data flows through a single register. The B-to-A data can flow through a four-stage pipeline register path, or through a single register path, depending on the state of the select ($\overline{SEL}$) input.

Data is stored in the internal registers on the low-to-high transition of the clock (CLK) input, provided that the appropriate $\overline{CLKEN}$ inputs are low. The A-to-B data transfer is synchronized to the CLKAB input, and B-to-A data transfer is synchronized with the CLK1BA and CLK2BA inputs.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16525 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)

$\overline{CLKENAB}$	1	56	$\overline{SEL}$
$\overline{OEAB}$	2	55	CLKAB
A1	3	54	B1
GND	4	53	GND
A2	5	52	B2
A3	6	51	B3
V_{CC}	7	50	V_{CC}
A4	8	49	B4
A5	9	48	B5
A6	10	47	B6
GND	11	46	GND
A7	12	45	B7
A8	13	44	B8
A9	14	43	B9
A10	15	42	B10
A11	16	41	B11
A12	17	40	B12
GND	18	39	GND
A13	19	38	B13
A14	20	37	B14
A15	21	36	B15
V_{CC}	22	35	V_{CC}
A16	23	34	B16
A17	24	33	B17
GND	25	32	GND
A18	26	31	B18
$\overline{OEBA}$	27	30	CLK1BA
$\overline{CLKENBA}$	28	29	CLK2BA

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SN74ALVCH16525

18-BIT REGISTERED BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

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Function Tables

A-TO-B STORAGE
($\overline{\text{OEAB}} = \text{L}$)

INPUTS			OUTPUT B
CLKENAB	CLKAB	A	
H	X	X	$\text{B}_0^\dagger$
L	$\uparrow$	L	L
L	$\uparrow$	H	H

$\dagger$ Output level before the indicated steady-state input conditions were established

B-TO-A STORAGE
($\overline{\text{OEBA}} = \text{L}$)

INPUTS					OUTPUT A
$\overline{\text{CLKENBA}}$	CLK2BA	CLK1BA	$\overline{\text{SEL}}$	B	
H	X	X	X	X	$\text{A}_0^\dagger$
L	$\uparrow$	X	H	L	L
L	$\uparrow$	X	H	H	H
L	$\uparrow$	$\uparrow$	L	L	$\text{L}^\ddagger$
L	$\uparrow$	$\uparrow$	L	H	$\text{H}^\ddagger$

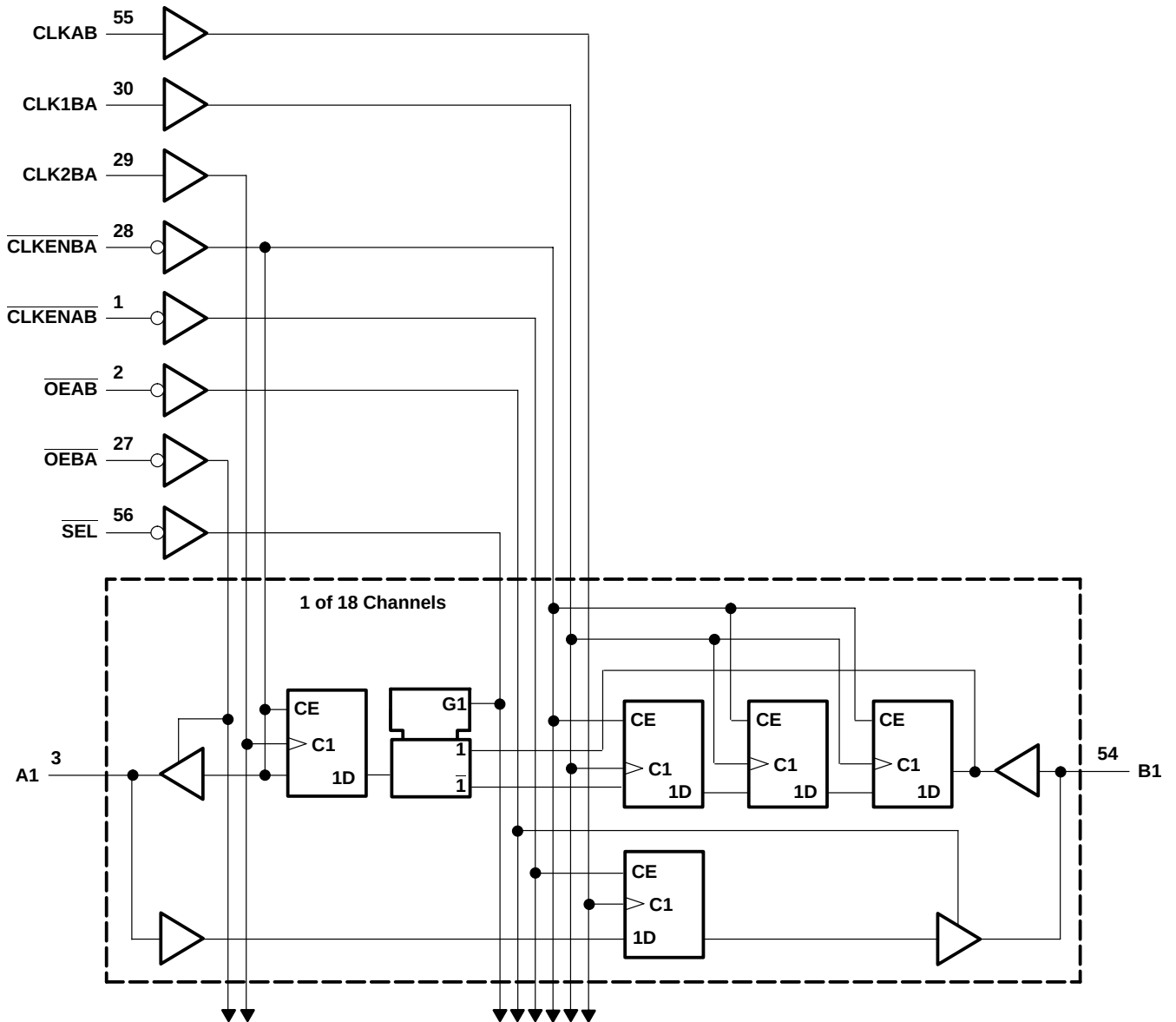
$\dagger$ Output level before the indicated steady-state input conditions were established

$\ddagger$ Three CLK1BA edges and one CLK2BA edge are needed to propagate data from B to A when $\overline{\text{SEL}}$ is low.

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logic diagram (positive logic)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
		I _{OL} = 12 mA	2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ} [§]		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3			pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V	7			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.



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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency	†		120		125		150		MHz
t _w	Pulse duration, CLK high or low	†		3.2		3.2		3		ns
t _{su}	Setup time	A data before CLKAB↑		†		1.3		1.3		ns
		B data before CLK2BA↑		†		2.1		1.8		
		B data before CLK1BA↑		†		1.3		1.2		
		SEL before CLK2BA↑		†		3.3		3.3		
		CLKENAB before CLKAB↑		†		2.1		1.9		
		CLKENBA before CLK1BA↑		†		2.7		2.5		
		CLKENBA before CLK2BA↑		†		2.7		2.5		
t _h	Hold time	A data after CLKAB↑		†		0.7		0.4		ns
		B data after CLK2BA↑		†		0.4		0		
		B data after CLK1BA↑		†		0.8		0.4		
		SEL after CLK2BA↑		†		0		0		
		CLKENAB after CLKAB↑		†		0.1		0.3		
		CLKENBA after CLK1BA↑		†		0		0		
		CLKENBA after CLK2BA↑		†		0		0		

† This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 1.8\text{ V}$		$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f_{max}			†		120		125		150		MHz
t_{pd}	CLKAB or CLK2BA	A or B	†		1	4.5	4.4		1	4.2	ns
t_{en}	$\overline{\text{OEAB}}$ or $\overline{\text{OEBA}}$	A or B	†		1	6.1	6.1		1	5.1	ns
t_{dis}	$\overline{\text{OEAB}}$ or $\overline{\text{OEBA}}$	A or B	†		1	6.3	5.4		1	4.9	ns

† This information was not available at the time of publication.

operating characteristics, $T_A = 25^\circ\text{C}$

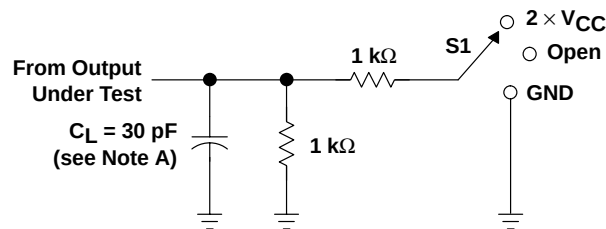
PARAMETER			TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
				TYP	TYP	TYP	
C_{pd}	Power dissipation capacitance	Outputs enabled	$C_L = 50\text{ pF}, f = 10\text{ MHz}$	†	160	160	pF
		Outputs disabled		†	160	160	

† This information was not available at the time of publication.



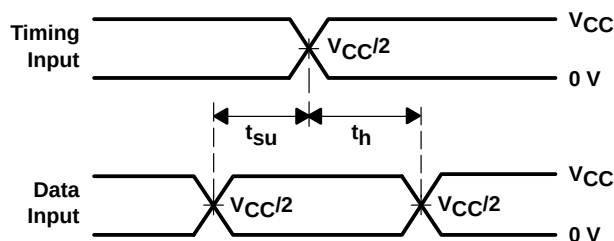
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$

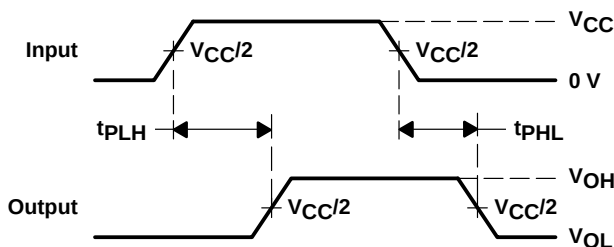


LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PHZ}	GND



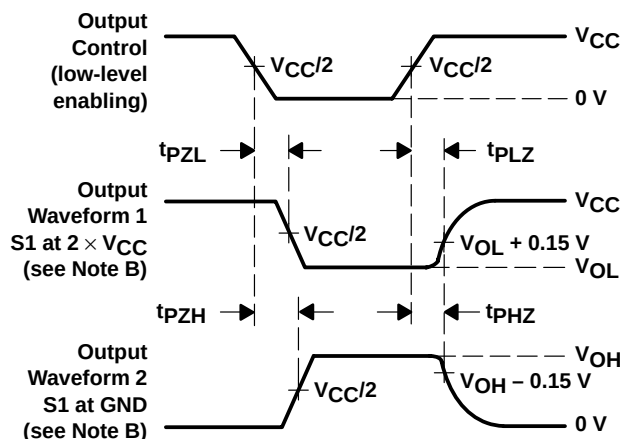
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

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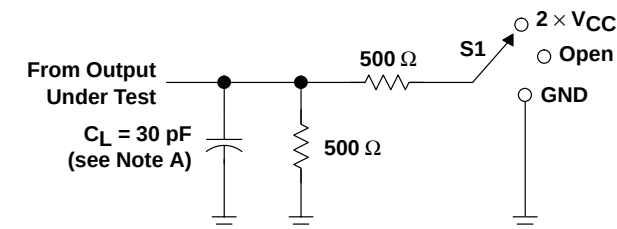
18-BIT REGISTERED BUS TRANSCEIVER

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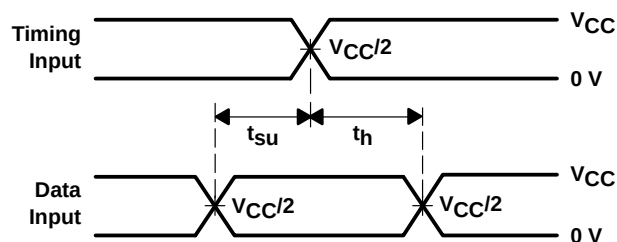
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

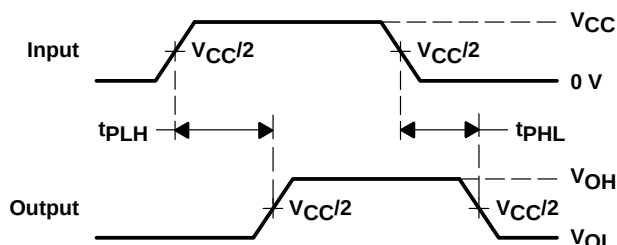


LOAD CIRCUIT

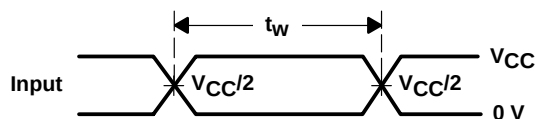
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



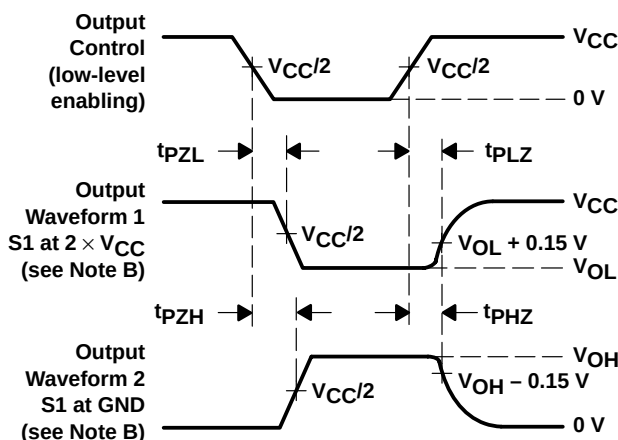
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



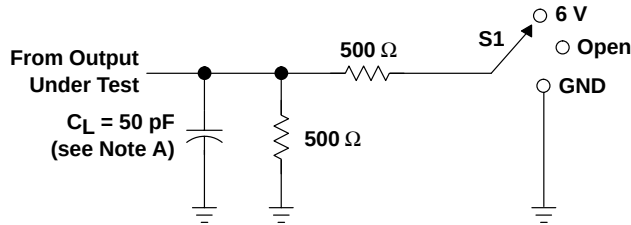
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

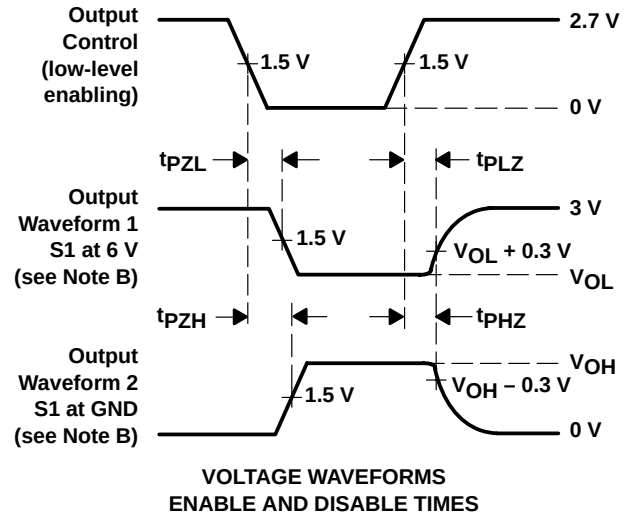
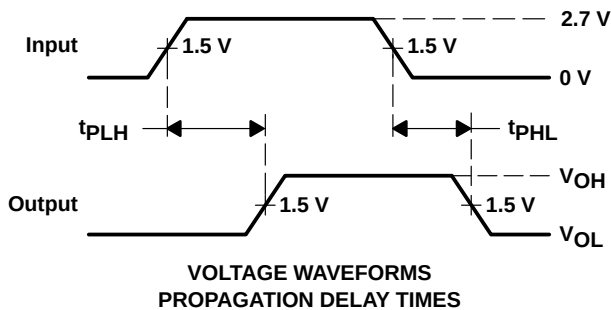
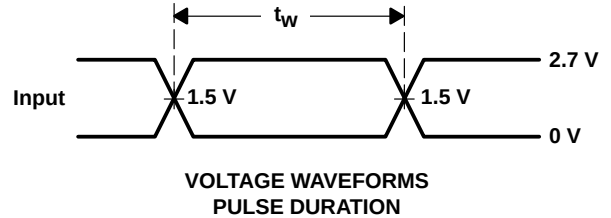
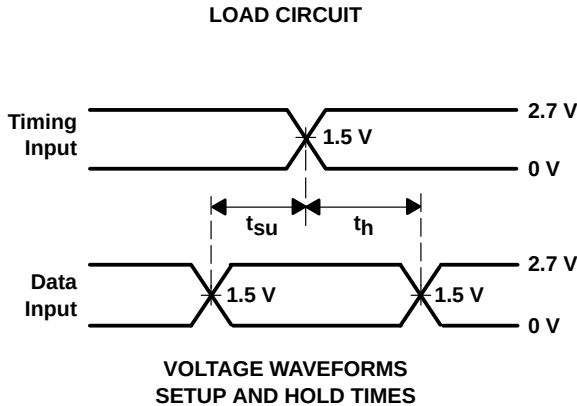
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dLZ} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16540 16-BIT BUFFER/DRIVER WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 16-bit buffer/driver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16540 provides a high-performance bus interface for wide data paths.

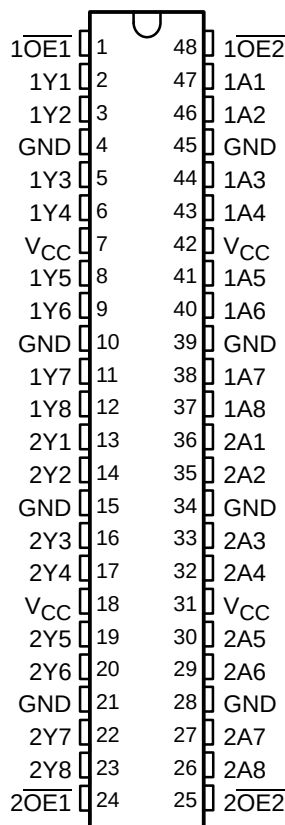
The 3-state control gate is a 2-input AND gate with active-low inputs so that if either output-enable ($\overline{OE1}$ or $\overline{OE2}$) input is high, all corresponding outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16540 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)



FUNCTION TABLE
(each 8-bit section)

INPUTS			OUTPUT Y
$\overline{OE1}$	$\overline{OE2}$	A	
L	L	L	H
L	L	H	L
H	X	X	Z
X	H	X	Z

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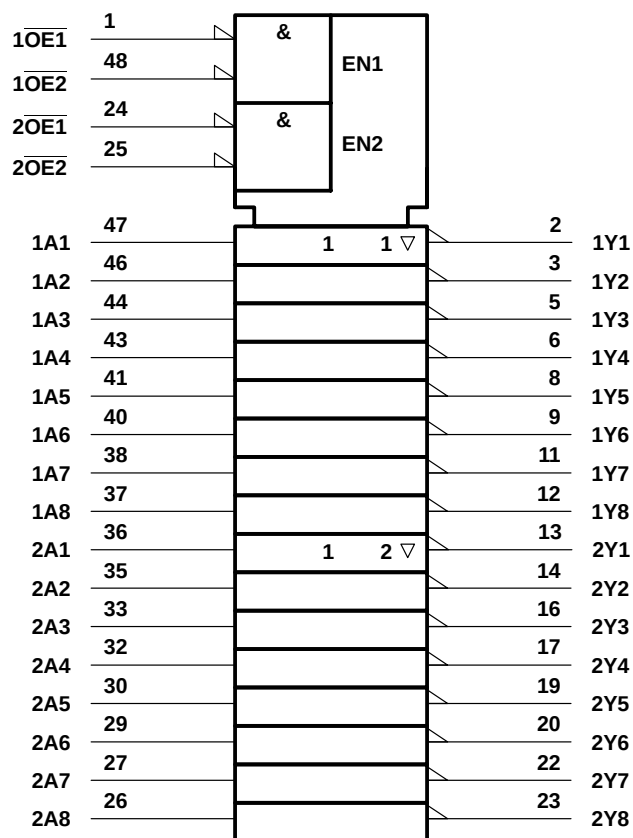
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SN74ALVCH16540 16-BIT BUFFER/DRIVER WITH 3-STATE OUTPUTS

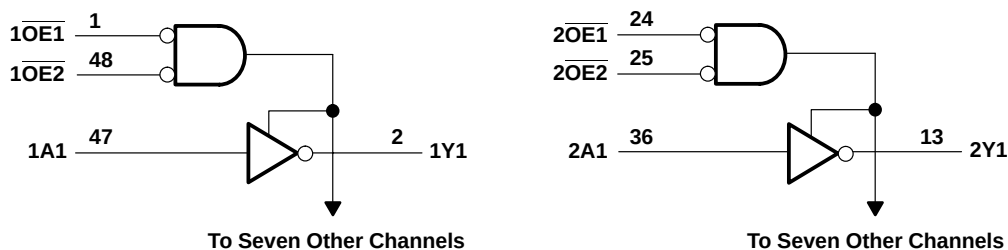
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logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	89°C/W
DL package	94°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

SN74ALVCH16540
16-BIT BUFFER/DRIVER
WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V			pF
	Data inputs					
C _O	Outputs	V _O = V _{CC} or GND	3.3 V			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	Y								ns
t _{en}	OE	Y								ns
t _{dis}	OE	Y								ns

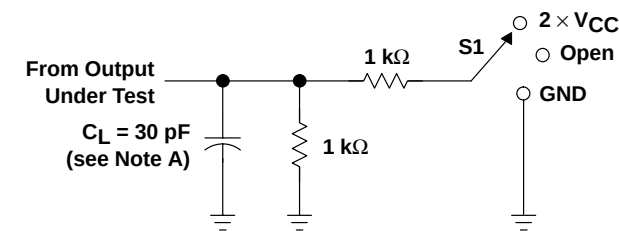


operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd} Power dissipation capacitance	Outputs enabled	$C_L = 0$, $f = 10\text{ MHz}$				pF
	Outputs disabled					

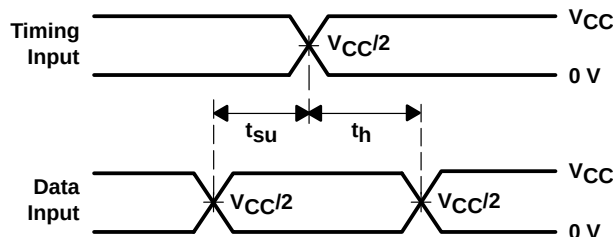
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8\text{ V}$

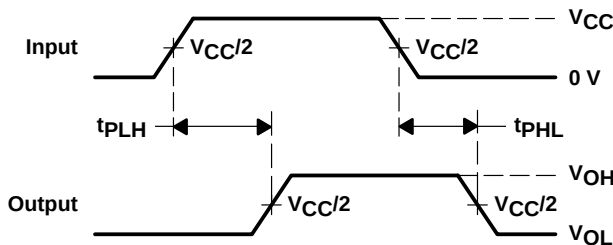


LOAD CIRCUIT

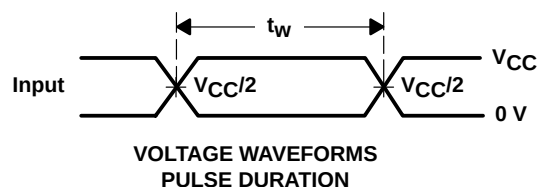
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	$2 \times V_{CC}$
t_{PHZ}/t_{PZH}	GND



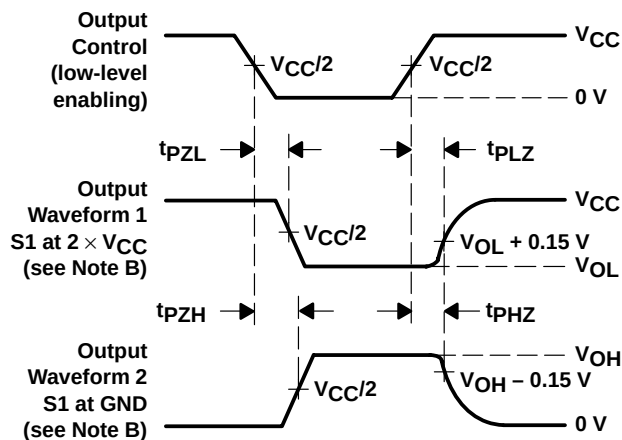
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION

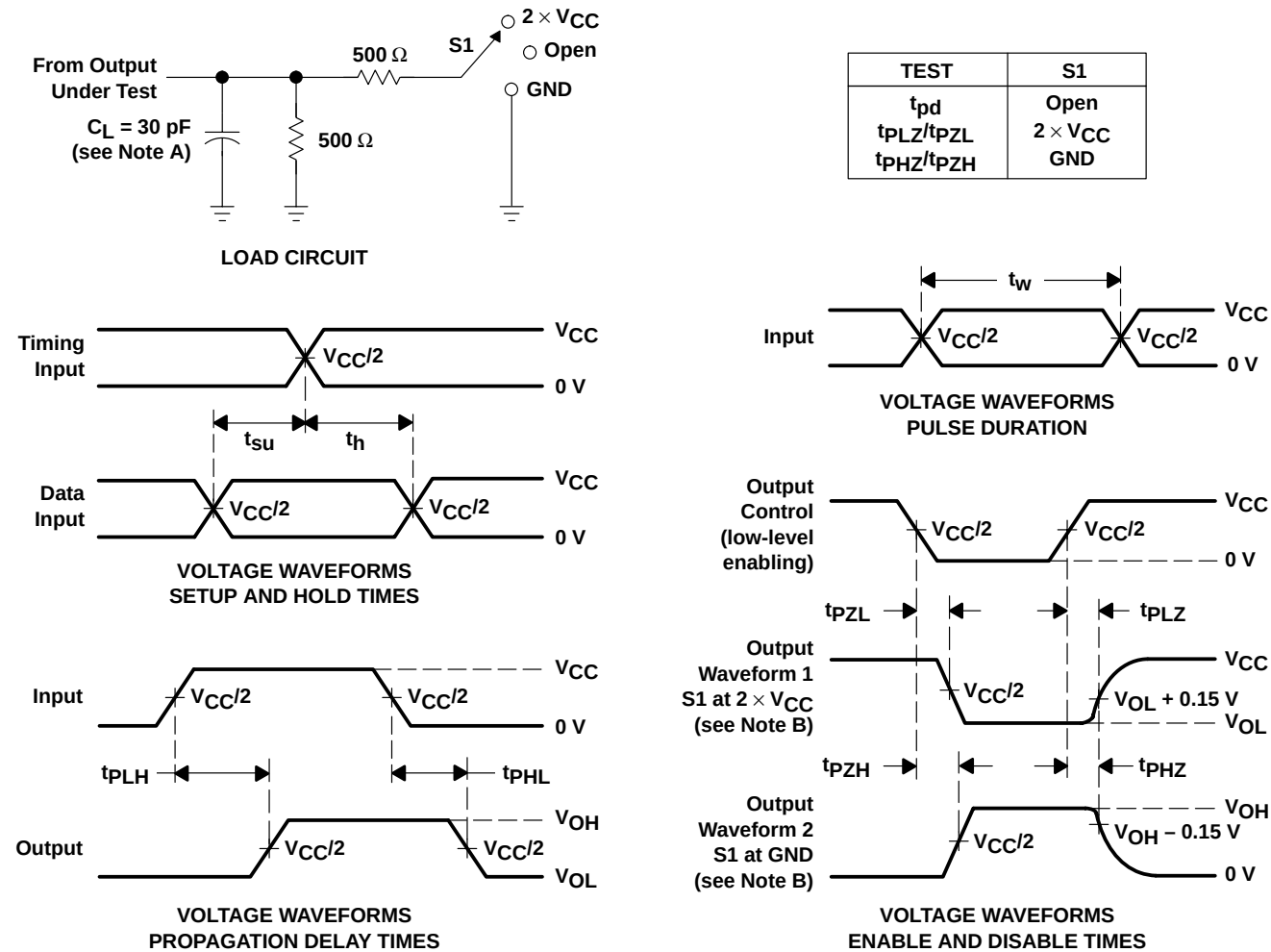


VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dLZ} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$

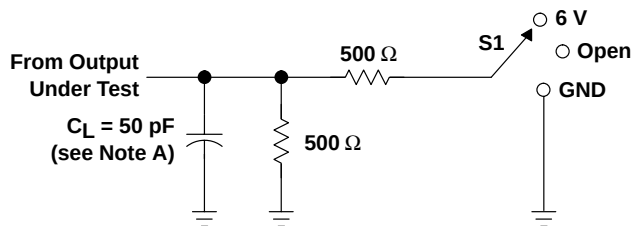


- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

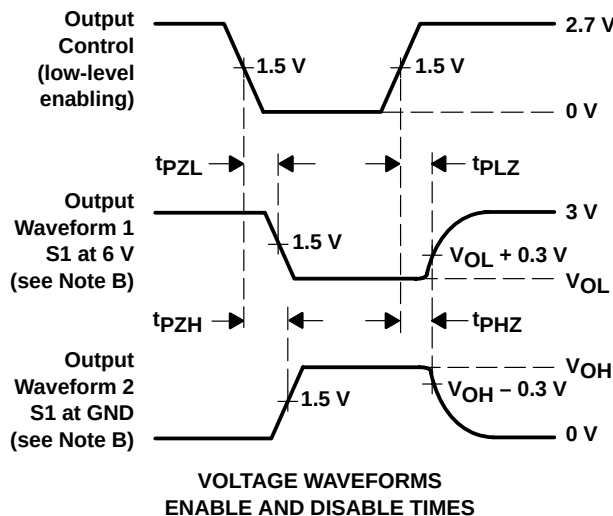
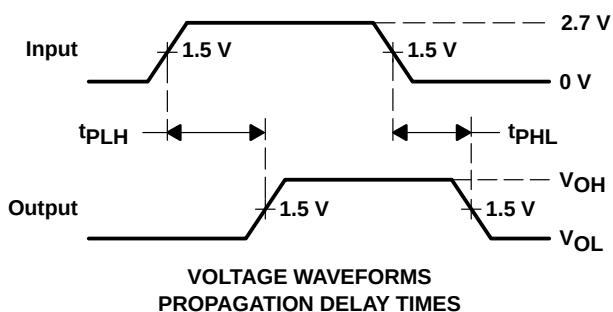
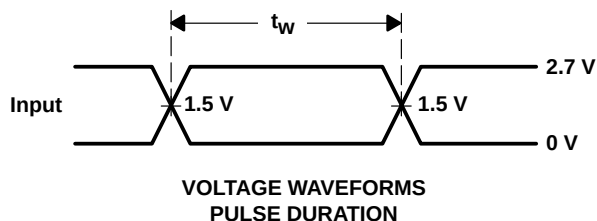
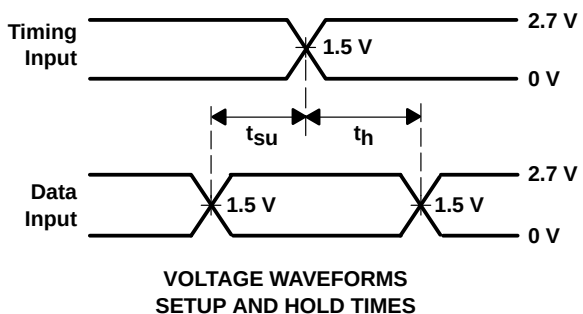
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dLZ} .
 - t_{PZL} and t_{PZH} are the same as t_{dLH} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16541 16-BIT BUFFER/DRIVER WITH 3-STATE OUTPUTS

SCES031B – JULY 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 16-bit buffer/driver is designed for 1.65-V to 3.6-V V_{CC} operation.

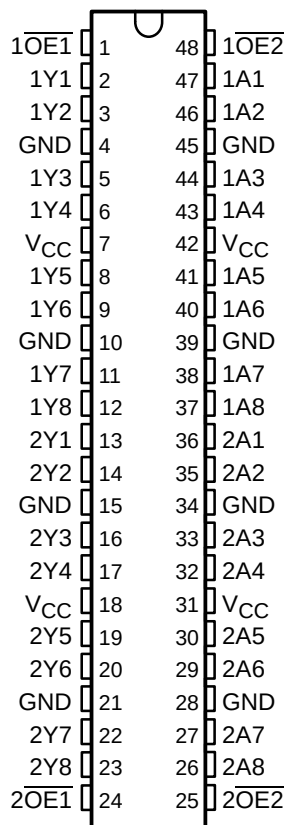
The SN74ALVCH16541 is a noninverting 16-bit buffer composed of two 8-bit sections with separate output-enable signals. For either 8-bit buffer section, the output enables ($\overline{1OE1}$ and $\overline{1OE2}$ or $\overline{2OE1}$ and $\overline{2OE2}$) must both be low for the corresponding Y outputs to be active. If either output-enable input is high, the outputs of that 8-bit buffer section are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16541 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)



FUNCTION TABLE
(each 8-bit section)

INPUTS			OUTPUT Y
$\overline{OE1}$	$\overline{OE2}$	A	
L	L	L	L
L	L	H	H
H	X	X	Z
X	H	X	Z

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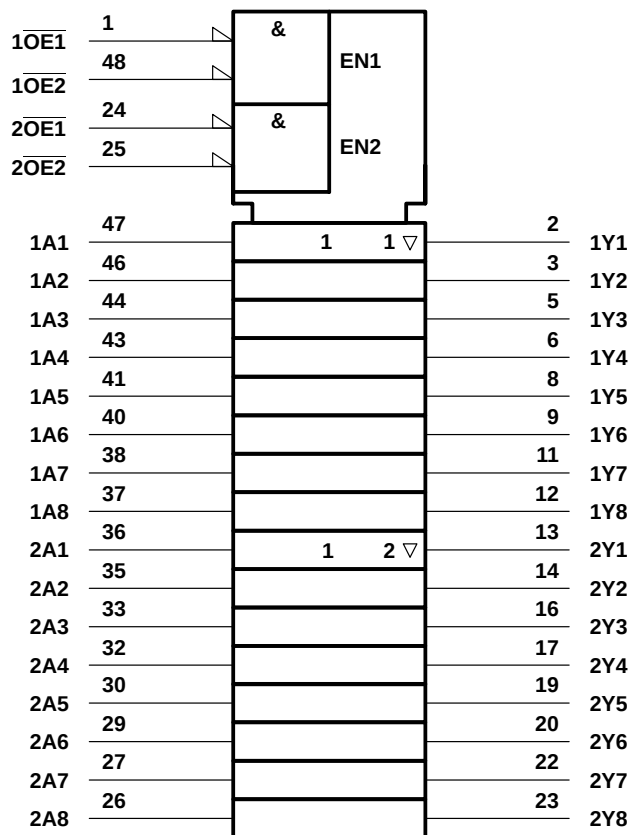
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SN74ALVCH16541 16-BIT BUFFER/DRIVER WITH 3-STATE OUTPUTS

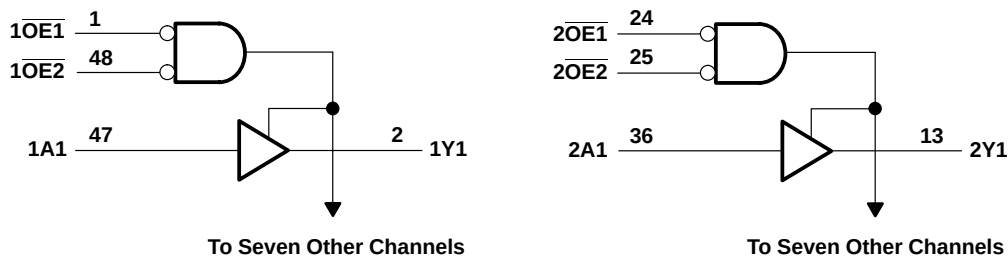
SCES031B – JULY 1995 – REVISED FEBRUARY 1999

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	89°C/W
DL package	94°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate			10	ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

SN74ALVCH16541
16-BIT BUFFER/DRIVER
WITH 3-STATE OUTPUTS

SCES031B – JULY 1995 – REVISED FEBRUARY 1999

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V			pF
	Data inputs					
C _O	Outputs	V _O = V _{CC} or GND	3.3 V			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	Y								ns
t _{en}	OE	Y								ns
t _{dis}	OE	Y								ns

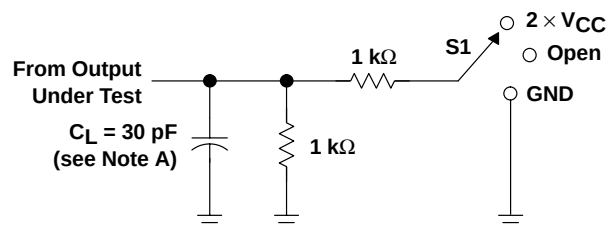


operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd} Power dissipation capacitance	Outputs enabled	$C_L = 0, f = 10\text{ MHz}$				pF
	Outputs disabled					

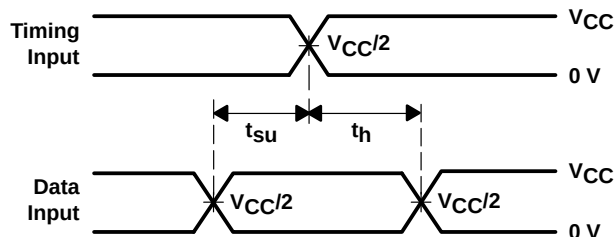
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8\text{ V}$

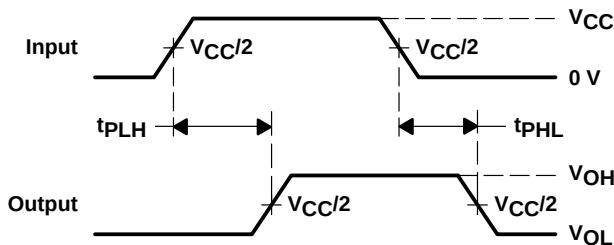


LOAD CIRCUIT

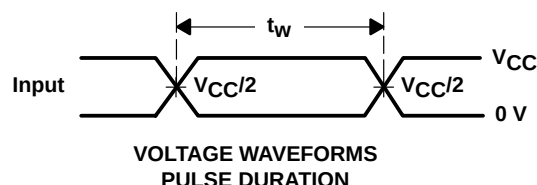
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



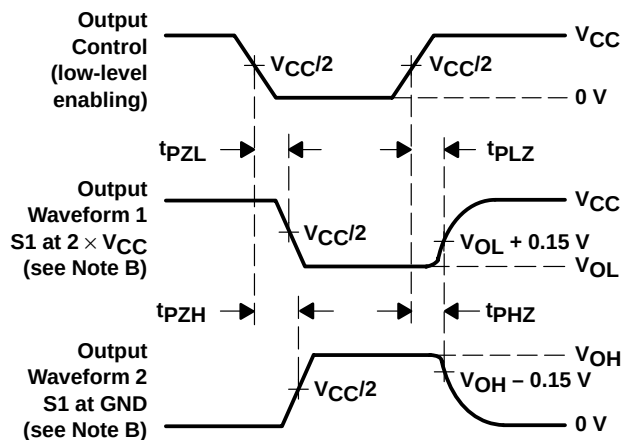
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: PRR $\leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dLS} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

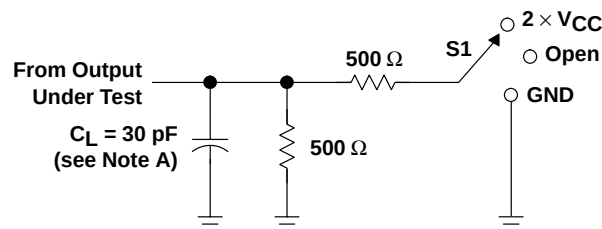
Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH16541 16-BIT BUFFER/DRIVER WITH 3-STATE OUTPUTS

SCES031B – JULY 1995 – REVISED FEBRUARY 1999

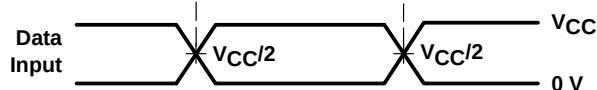
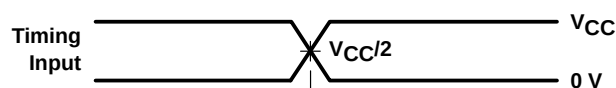
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

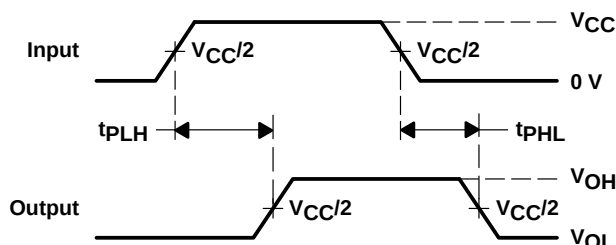


LOAD CIRCUIT

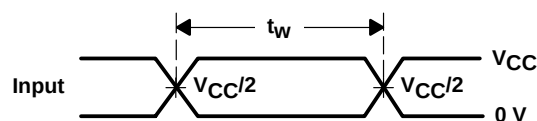
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



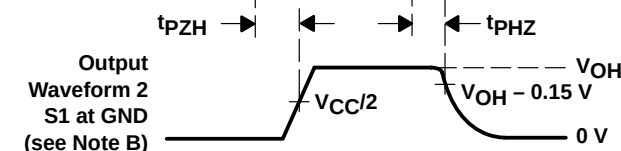
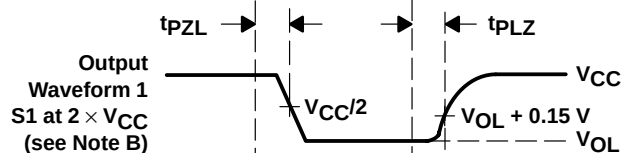
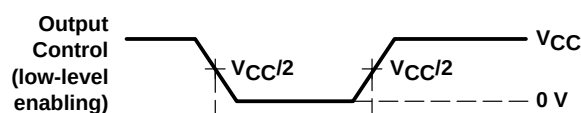
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



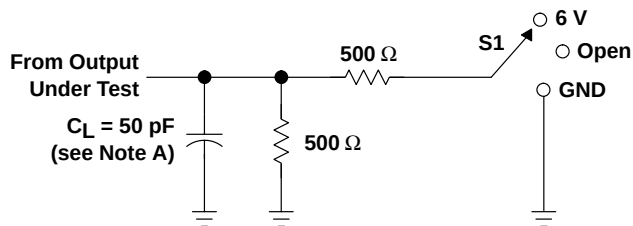
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

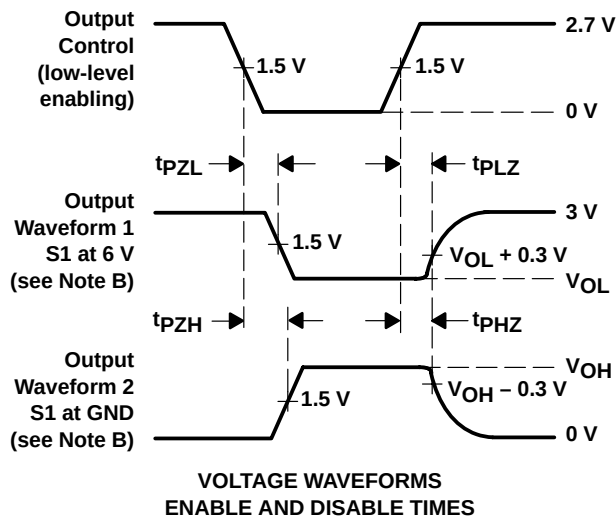
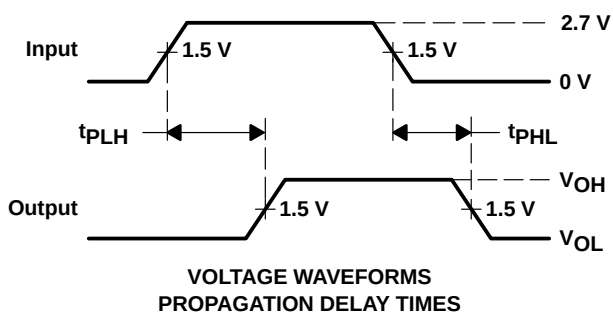
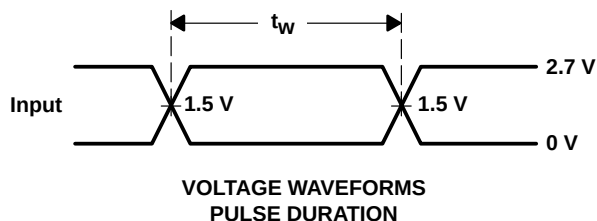
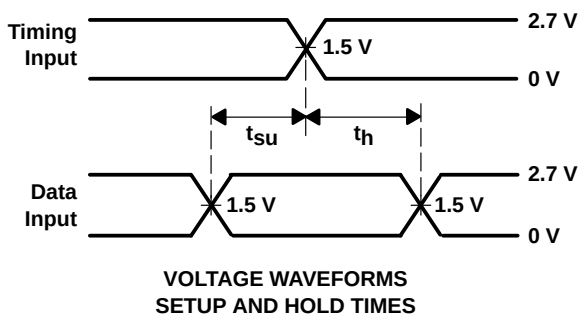
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dLZ} .
 - t_{PZL} and t_{PZH} are the same as t_{dLH} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16543

16-BIT REGISTERED TRANSCEIVER WITH 3-STATE OUTPUTS

SCES025D – JULY 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 16-bit registered transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16543 can be used as two 8-bit transceivers or one 16-bit transceiver. Separate latch-enable ($\overline{LEAB}$ or $\overline{LEBA}$) and output-enable ($\overline{OEAB}$ or $\overline{OEBA}$) inputs are provided for each register to permit independent control in either direction of data flow.

The A-to-B enable ($\overline{CEAB}$) input must be low to enter data from A or to output data from B. If $\overline{CEAB}$ is low and $\overline{LEAB}$ is low, the A-to-B latches are transparent; a subsequent low-to-high transition of $\overline{LEAB}$ puts the A latches in the storage mode. With $\overline{CEAB}$ and $\overline{OEAB}$ both low, the 3-state B outputs are active and reflect the data present at the output of the A latches. Data flow from B to A is similar, but requires using $\overline{CEBA}$, $\overline{LEBA}$, and $\overline{OEBA}$.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16543 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)

$\overline{1OEAB}$	1	56	$\overline{1OEBA}$
$\overline{1LEAB}$	2	55	$\overline{1LEBA}$
$\overline{1CEAB}$	3	54	$\overline{1CEBA}$
GND	4	53	GND
1A1	5	52	1B1
1A2	6	51	1B2
V_{CC}	7	50	V_{CC}
1A3	8	49	1B3
1A4	9	48	1B4
1A5	10	47	1B5
GND	11	46	GND
1A6	12	45	1B6
1A7	13	44	1B7
1A8	14	43	1B8
2A1	15	42	2B1
2A2	16	41	2B2
2A3	17	40	2B3
GND	18	39	GND
2A4	19	38	2B4
2A5	20	37	2B5
2A6	21	36	2B6
V_{CC}	22	35	V_{CC}
2A7	23	34	2B7
2A8	24	33	2B8
GND	25	32	GND
$\overline{2CEAB}$	26	31	$\overline{2CEBA}$
$\overline{2LEAB}$	27	30	$\overline{2LEBA}$
$\overline{2OEAB}$	28	29	$\overline{2OEBA}$

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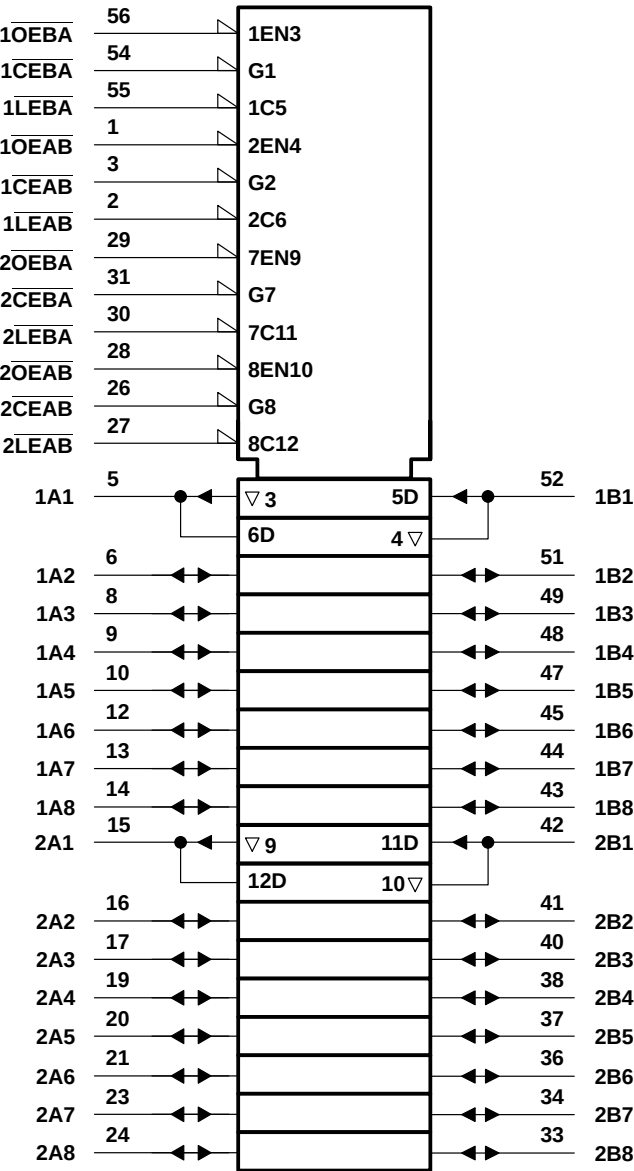
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SN74ALVCH16543
16-BIT REGISTERED TRANSCEIVER
WITH 3-STATE OUTPUTS

SCES025D – JULY 1995 – REVISED FEBRUARY 1999

logic symbol†

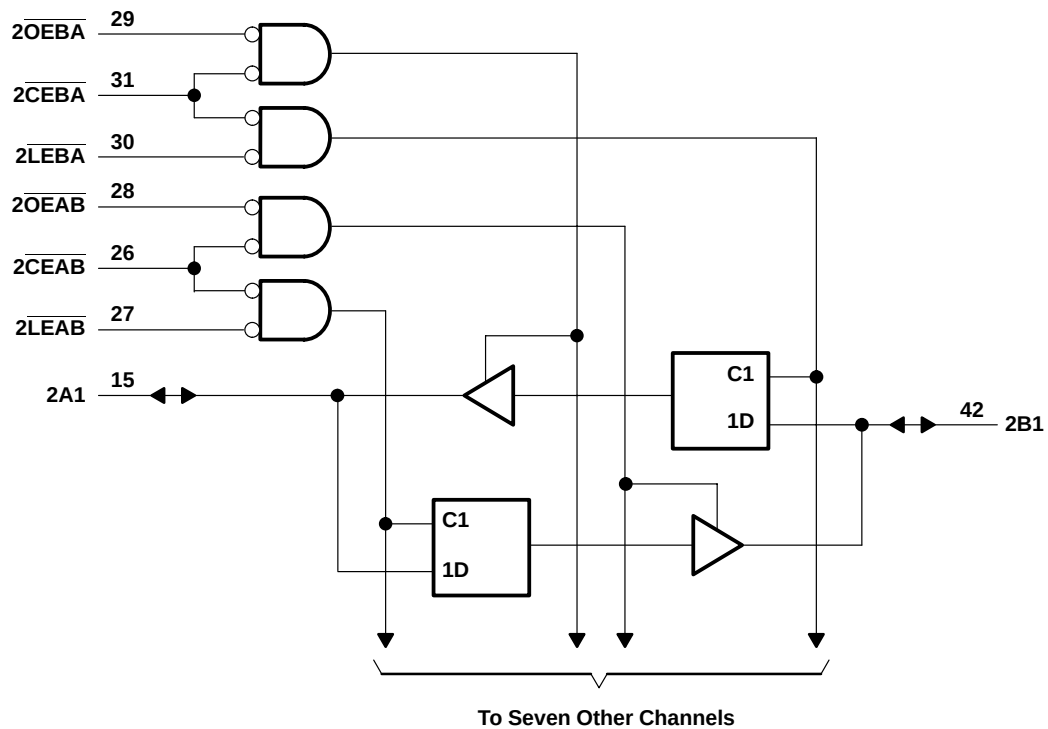
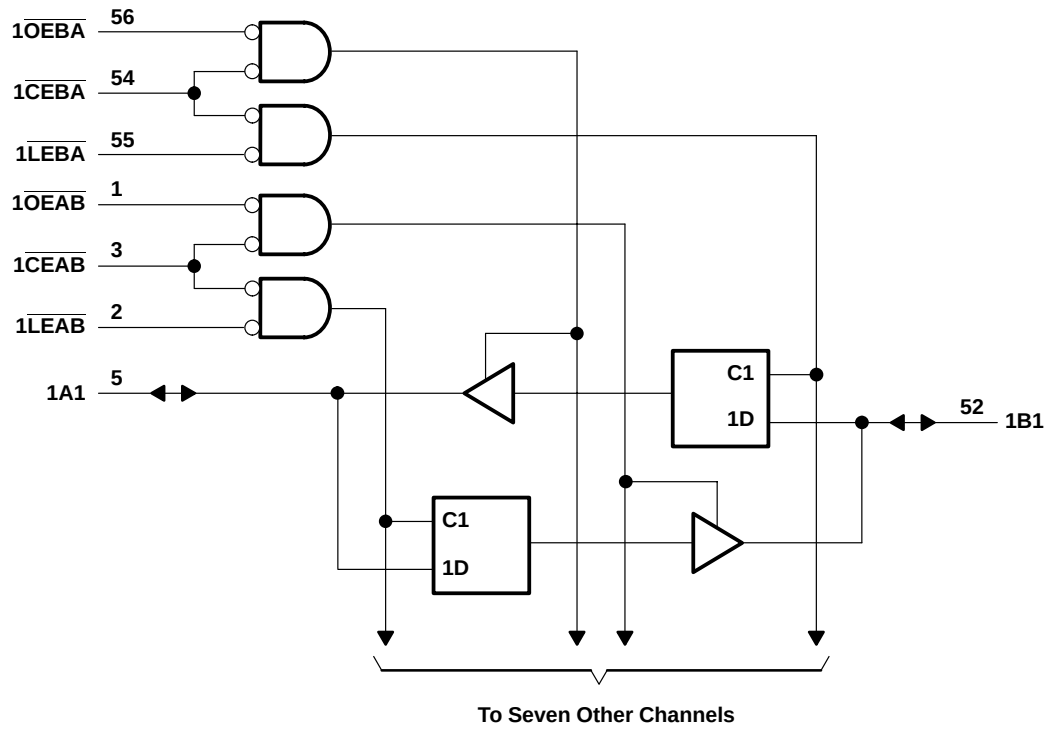


† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

SN74ALVCH16543
16-BIT REGISTERED TRANSCEIVER
WITH 3-STATE OUTPUTS

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logic diagram (positive logic)



SN74ALVCH16543
16-BIT REGISTERED TRANSCEIVER
WITH 3-STATE OUTPUTS

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FUNCTION TABLE†
(each 8-bit section)

INPUTS				OUTPUT B
CEAB	LEAB	OEAB	A	
H	X	X	X	Z
X	X	H	X	Z
L	H	L	X	B ₀ ‡
L	L	L	L	L
L	L	L	H	H

† A-to-B data flow is shown; B-to-A flow control is the same except that it uses $\overline{\text{CEBA}}$, $\overline{\text{LEBA}}$, and $\overline{\text{OEBA}}$.

‡ Output level before the indicated steady-state input conditions were established

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)§

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	65°C to 150°C

§ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

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16-BIT REGISTERED TRANSCEIVER
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recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate			10	ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 μA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA		2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 μA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA		2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V	±5			μA
I _I (hold)		V _I = 0.58 V	1.65 V	25			μA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
	I _{OZ} [§]		V _O = V _{CC} or GND	3.6 V	±10		
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			μA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			μA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3.5			pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V	8.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t _w	Pulse duration, $\overline{\text{LE}}$ or $\overline{\text{CE}}$ low	¶		3.3		3.3		3.3		ns
t _{su}	Setup time	Data before $\overline{\text{LE}}\uparrow$ or $\overline{\text{CE}}\uparrow$		1.2		1.5		1.2		ns
t _h	Hold time	Data after $\overline{\text{LE}}\uparrow$ or $\overline{\text{CE}}\uparrow$		1.2		0.8		1.3		ns

¶ This information was not available at the time of publication.



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16-BIT REGISTERED TRANSCEIVER
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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A or B	B or A	†	1	5.1	4.8		1	4.3	ns
	$\overline{LE}$	A or B	†	1	6.5	6.2		1.1	5	
t _{en}	$\overline{CE}$	A or B	†	1	7.2	6.9		1	5.6	ns
t _{dis}	$\overline{CE}$	A or B	†	1.3	6.1	6.2		1.5	5.1	ns
t _{en}	$\overline{OE}$	A or B	†	1	6.8	6.3		1	5.3	ns
t _{dis}	$\overline{OE}$	A or B	†	1	5.7	4.8		1.1	4.6	ns

† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 50 pF, f = 10 MHz	†	54	64	pF
		Outputs disabled		†	6	7	

† This information was not available at the time of publication.



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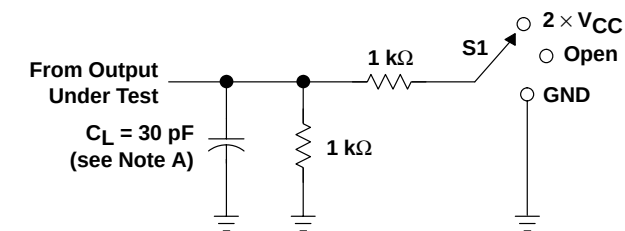
16-BIT REGISTERED TRANSCEIVER

WITH 3-STATE OUTPUTS

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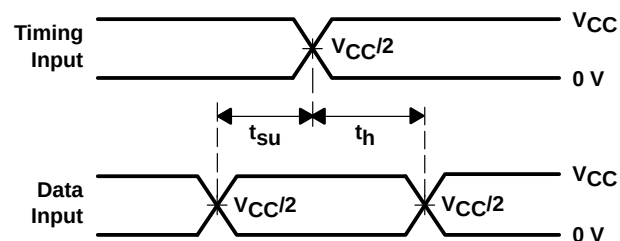
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$

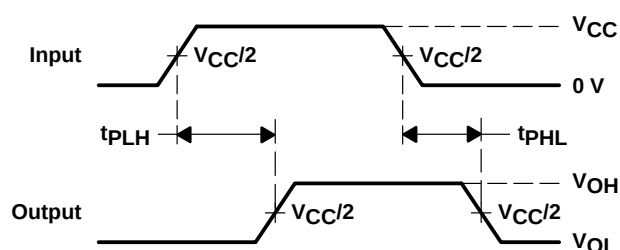


LOAD CIRCUIT

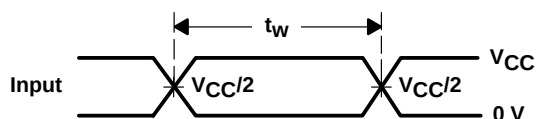
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



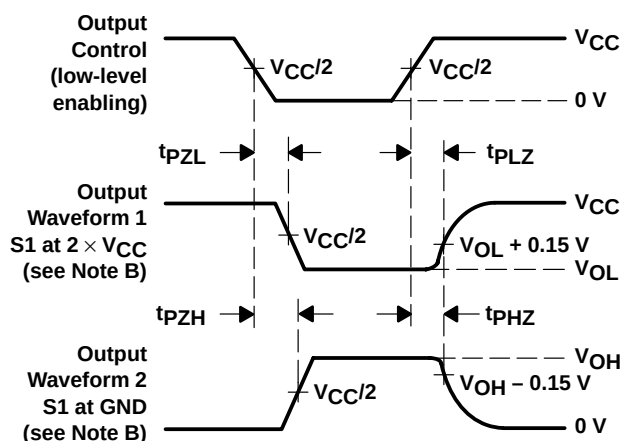
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



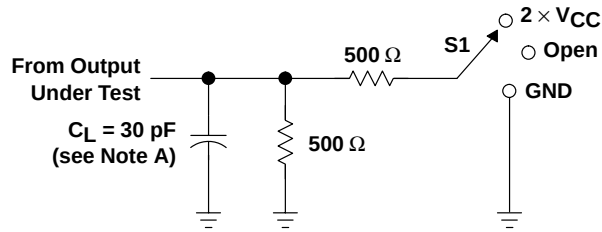
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

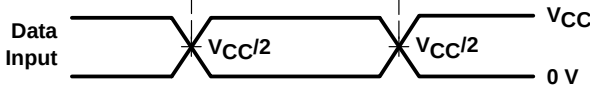
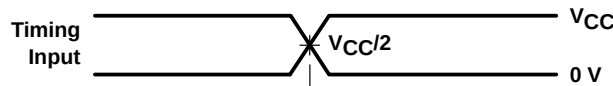
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

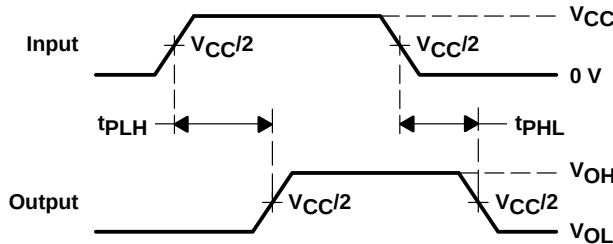


LOAD CIRCUIT

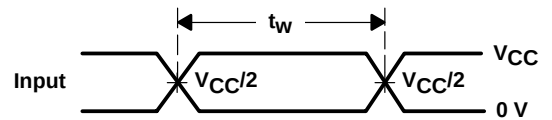
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times$ V_{CC}
t_{PHZ}/t_{PZH}	GND



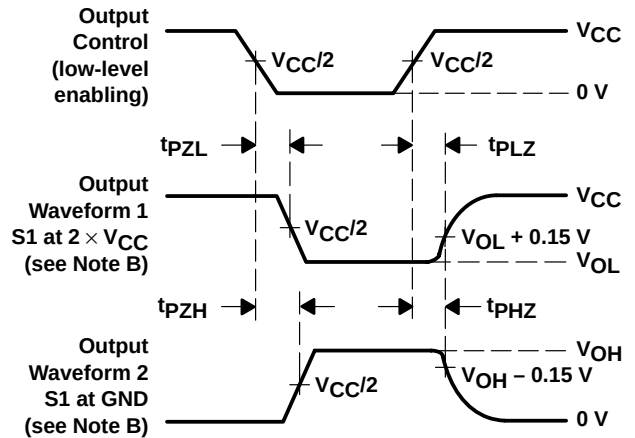
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
D. The outputs are measured one at a time with one transition per measurement.
E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
F. t_{PZL} and t_{PZH} are the same as t_{en} .
G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH16543

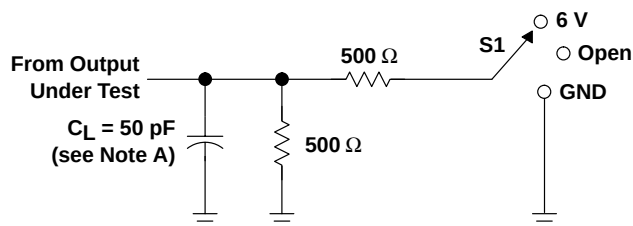
16-BIT REGISTERED TRANSCEIVER

WITH 3-STATE OUTPUTS

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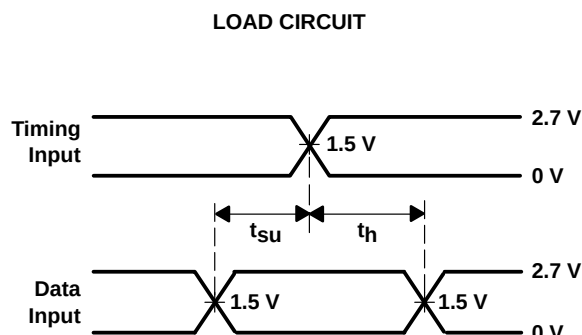
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$

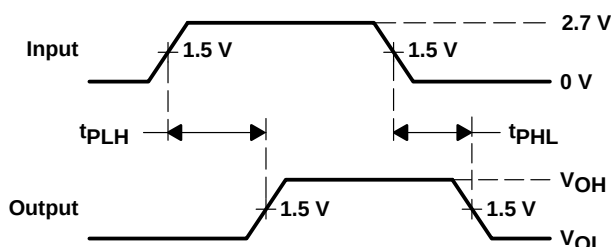


LOAD CIRCUIT

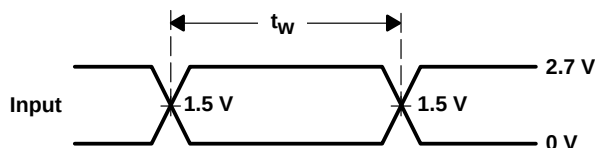
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



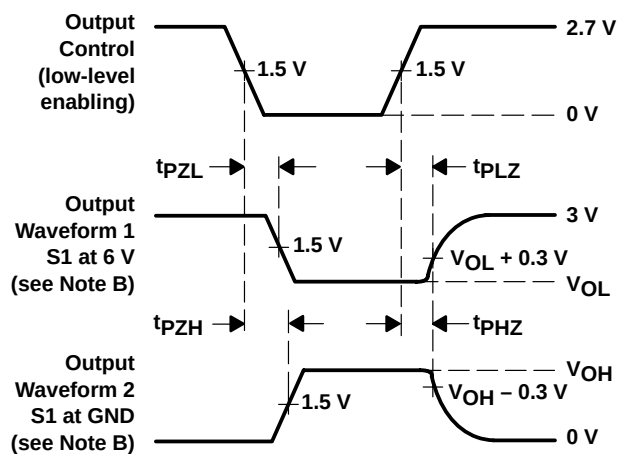
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16600

18-BIT UNIVERSAL BUS TRANSCEIVER WITH 3-STATE OUTPUTS

SCES030D – JULY 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- *UBT™* (Universal Bus Transceiver) Combines D-Type Latches and D-Type Flip-Flops for Operation in Transparent, Latched, Clocked, or Clock-Enabled Mode
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 18-bit universal bus transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16600 combines D-type latches and D-type flip-flops to allow data flow in transparent, latched, and clocked modes.

Data flow in each direction is controlled by output-enable ($\overline{OEAB}$ and $\overline{OEBA}$), latch-enable ($\overline{LEAB}$ and $\overline{LEBA}$), and clock ($\overline{CLKAB}$ and $\overline{CLKBA}$) inputs. The clock can be controlled by the clock-enable ($\overline{CLKENAB}$ and $\overline{CLKENBA}$) inputs. For A-to-B data flow, the device operates in the transparent mode when $\overline{LEAB}$ is high. When $\overline{LEAB}$ is low, the A data is latched if $\overline{CLKAB}$ is held at a high or low logic level. If $\overline{LEAB}$ is low, the A data is stored in the latch/flip-flop on the high-to-low transition of $\overline{CLKAB}$. Output enable $\overline{OEAB}$ is active low. When $\overline{OEAB}$ is low, the outputs are active. When $\overline{OEAB}$ is high, the outputs are in the high-impedance state.

Data flow for B to A is similar to that of A to B but uses $\overline{OEBA}$, $\overline{LEBA}$, $\overline{CLKBA}$, and $\overline{CLKENBA}$.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16600 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)

$\overline{OEAB}$	1	56	$\overline{CLKENAB}$
$\overline{LEAB}$	2	55	$\overline{CLKAB}$
A1	3	54	B1
GND	4	53	GND
A2	5	52	B2
A3	6	51	B3
V_{CC}	7	50	V_{CC}
A4	8	49	B4
A5	9	48	B5
A6	10	47	B6
GND	11	46	GND
A7	12	45	B7
A8	13	44	B8
A9	14	43	B9
A10	15	42	B10
A11	16	41	B11
A12	17	40	B12
GND	18	39	GND
A13	19	38	B13
A14	20	37	B14
A15	21	36	B15
V_{CC}	22	35	V_{CC}
A16	23	34	B16
A17	24	33	B17
GND	25	32	GND
A18	26	31	B18
$\overline{OEBA}$	27	30	$\overline{CLKBA}$
$\overline{LEBA}$	28	29	$\overline{CLKENBA}$

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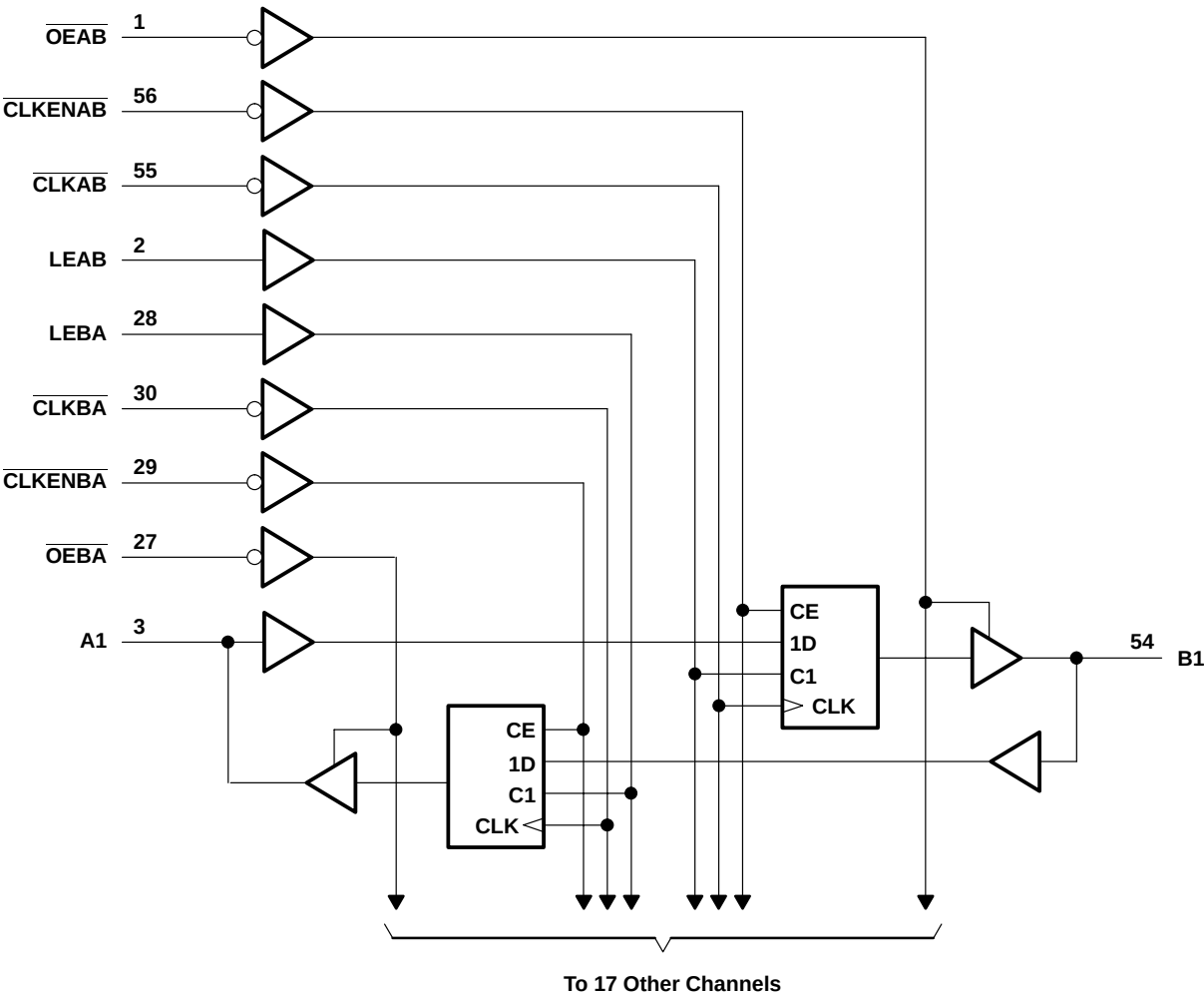
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FUNCTION TABLE†					
INPUTS					OUTPUT B
CLKENAB	OEAB	LEAB	CLKAB	A	
X	H	X	X	X	Z
X	L	H	X	L	L
X	L	H	X	H	H
H	L	L	X	X	B ₀ ‡
H	L	L	X	X	B ₀ ‡
L	L	L	↓	L	L
L	L	L	↓	H	H
L	L	L	L or H	X	B ₀ ‡

† A-to-B data flow is shown: B-to-A flow is similar but uses OEBA, LEBA, CLKBA, and CLKENBA.

‡ Output level before the indicated steady-state input conditions were established

logic diagram (positive logic)



SN74ALVCH16600
18-BIT UNIVERSAL BUS TRANSCEIVER
WITH 3-STATE OUTPUTS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ} [§]	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V		4	pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V		8	pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.



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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			$V_{CC} = 1.8\text{ V}$		$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f_{clock}	Clock frequency			†		150		150		150	MHz
t_w	Pulse duration	LE high		†		3.3		3.3		3.3	ns
		$\overline{\text{CLK}}$ high or low		†		3.3		3.3		3.3	
t_{su}	Setup time	Data before $\overline{\text{CLK}}\uparrow$		†		1.3		1.3		1.2	ns
		Data before LE $\downarrow$		†		1.2		1.1		1.1	
				†		1.8		1.5		1.5	
		$\overline{\text{CLKEN}}$ before $\overline{\text{CLK}}\uparrow$		†		0.7		0.7		0.8	
t_h	Hold time	Data after $\overline{\text{CLK}}\uparrow$		†		1.5		1.8		1.5	ns
		Data after LE $\downarrow$		†		1.6		1.9		1.6	
				†		1.2		1.6		1.3	
		$\overline{\text{CLKEN}}$ after $\overline{\text{CLK}}\uparrow$		†		1.4		1.7		1.4	

† This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 1.8\text{ V}$		$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f_{max}				†		150		150		150	MHz
t_{pd}	A or B	B or A		†		1	5.1		4.7		ns
	LEAB or LEBA	A or B		†		1	5.9		5.5		
	$\overline{\text{CLKAB}}$ or $\overline{\text{CLKBA}}$			†		1	7.3		6.8		
t_{en}	$\overline{\text{OEAB}}$ or $\overline{\text{OEBA}}$	A or B		†		1	6.5		6.3		ns
t_{dis}	$\overline{\text{OEAB}}$ or $\overline{\text{OEBA}}$	A or B		†		1	5.1		4.7		ns

† This information was not available at the time of publication.

operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER			TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
				TYP	TYP	TYP	
C_{pd}	Power dissipation capacitance	Outputs enabled	$C_L = 50\text{ pF}, f = 10\text{ MHz}$	†	43	56	pF
		Outputs disabled		†	6	6	

† This information was not available at the time of publication.

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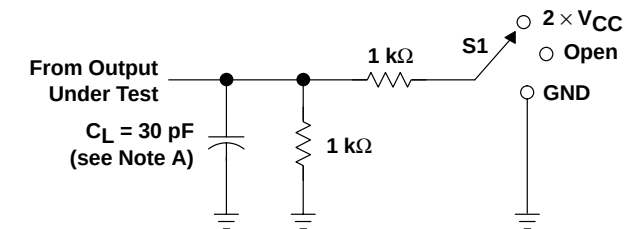
18-BIT UNIVERSAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

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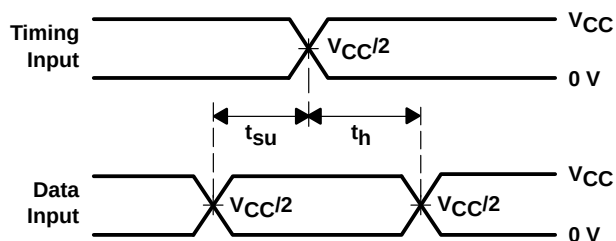
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8\text{ V}$

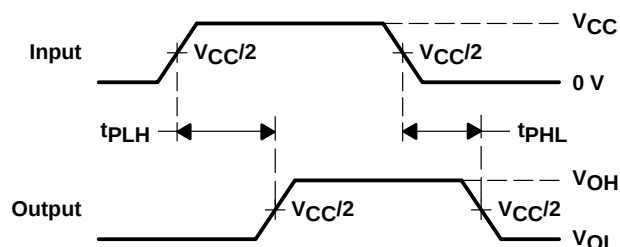


LOAD CIRCUIT

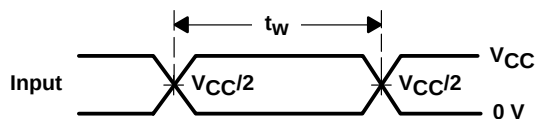
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	$2 \times V_{CC}$
t_{PHZ}/t_{PZH}	GND



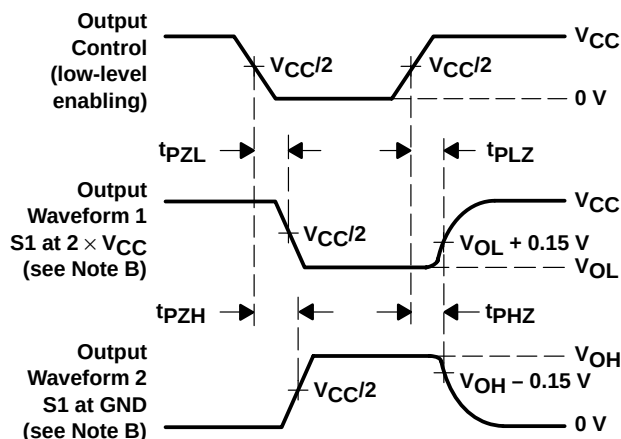
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



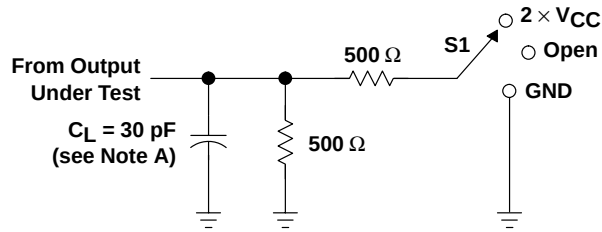
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

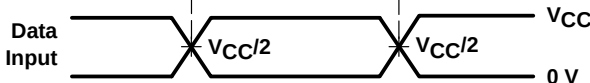
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

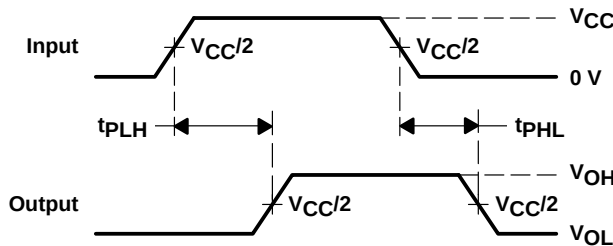


LOAD CIRCUIT

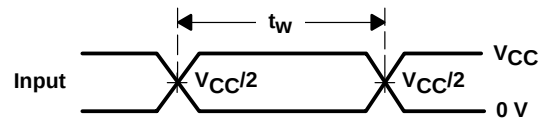
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



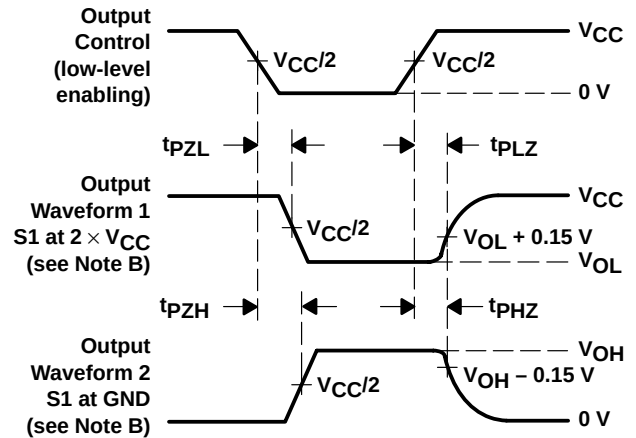
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
D. The outputs are measured one at a time with one transition per measurement.
E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
F. t_{PZL} and t_{PZH} are the same as t_{en} .
G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

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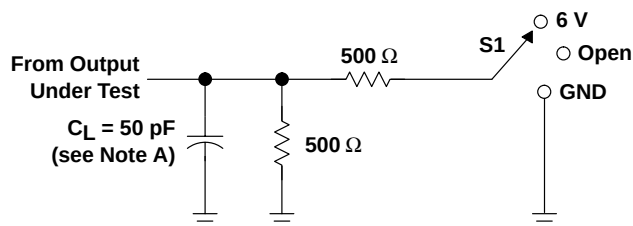
18-BIT UNIVERSAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

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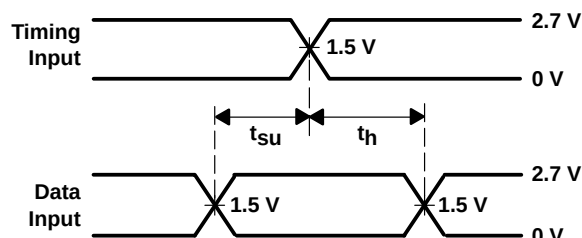
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

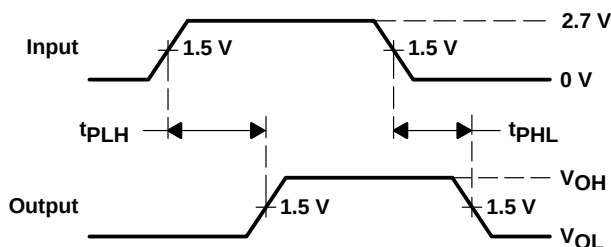


LOAD CIRCUIT

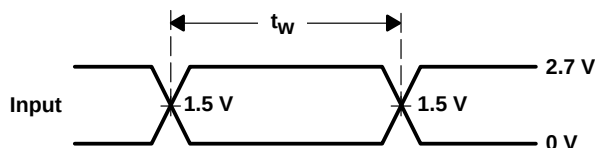
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



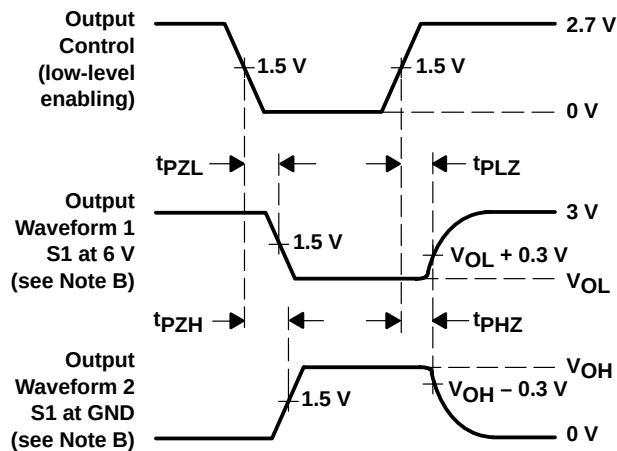
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16601

18-BIT UNIVERSAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus™* Family
- *UBT™* (Universal Bus Transceiver) Combines D-Type Latches and D-Type Flip-Flops for Operation in Transparent, Latched, Clocked, or Clock-Enabled Mode
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 18-bit universal bus transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16601 combines D-type latches and D-type flip-flops to allow data flow in transparent, latched, and clocked modes.

Data flow in each direction is controlled by output-enable ($\overline{OEAB}$ and $\overline{OEBA}$), latch-enable ($\overline{LEAB}$ and $\overline{LEBA}$), and clock ($\overline{CLKAB}$ and $\overline{CLKBA}$) inputs. The clock can be controlled by the clock-enable ($\overline{CLKENAB}$ and $\overline{CLKENBA}$) inputs. For A-to-B data flow, the device operates in the transparent mode when $\overline{LEAB}$ is high. When $\overline{LEAB}$ is low, the A data is latched if $\overline{CLKAB}$ is held at a high or low logic level. If $\overline{LEAB}$ is low, the A data is stored in the latch/flip-flop on the low-to-high transition of $\overline{CLKAB}$. Output enable $\overline{OEAB}$ is active low. When $\overline{OEAB}$ is low, the outputs are active. When $\overline{OEAB}$ is high, the outputs are in the high-impedance state.

Data flow for B to A is similar to that of A to B, but uses $\overline{OEBA}$, $\overline{LEBA}$, $\overline{CLKBA}$, and $\overline{CLKENBA}$.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16601 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)

$\overline{OEAB}$	1	56	$\overline{CLKENAB}$
$\overline{LEAB}$	2	55	$\overline{CLKAB}$
A1	3	54	B1
GND	4	53	GND
A2	5	52	B2
A3	6	51	B3
V_{CC}	7	50	V_{CC}
A4	8	49	B4
A5	9	48	B5
A6	10	47	B6
GND	11	46	GND
A7	12	45	B7
A8	13	44	B8
A9	14	43	B9
A10	15	42	B10
A11	16	41	B11
A12	17	40	B12
GND	18	39	GND
A13	19	38	B13
A14	20	37	B14
A15	21	36	B15
V_{CC}	22	35	V_{CC}
A16	23	34	B16
A17	24	33	B17
GND	25	32	GND
A18	26	31	B18
$\overline{OEBA}$	27	30	$\overline{CLKBA}$
$\overline{LEBA}$	28	29	$\overline{CLKENBA}$

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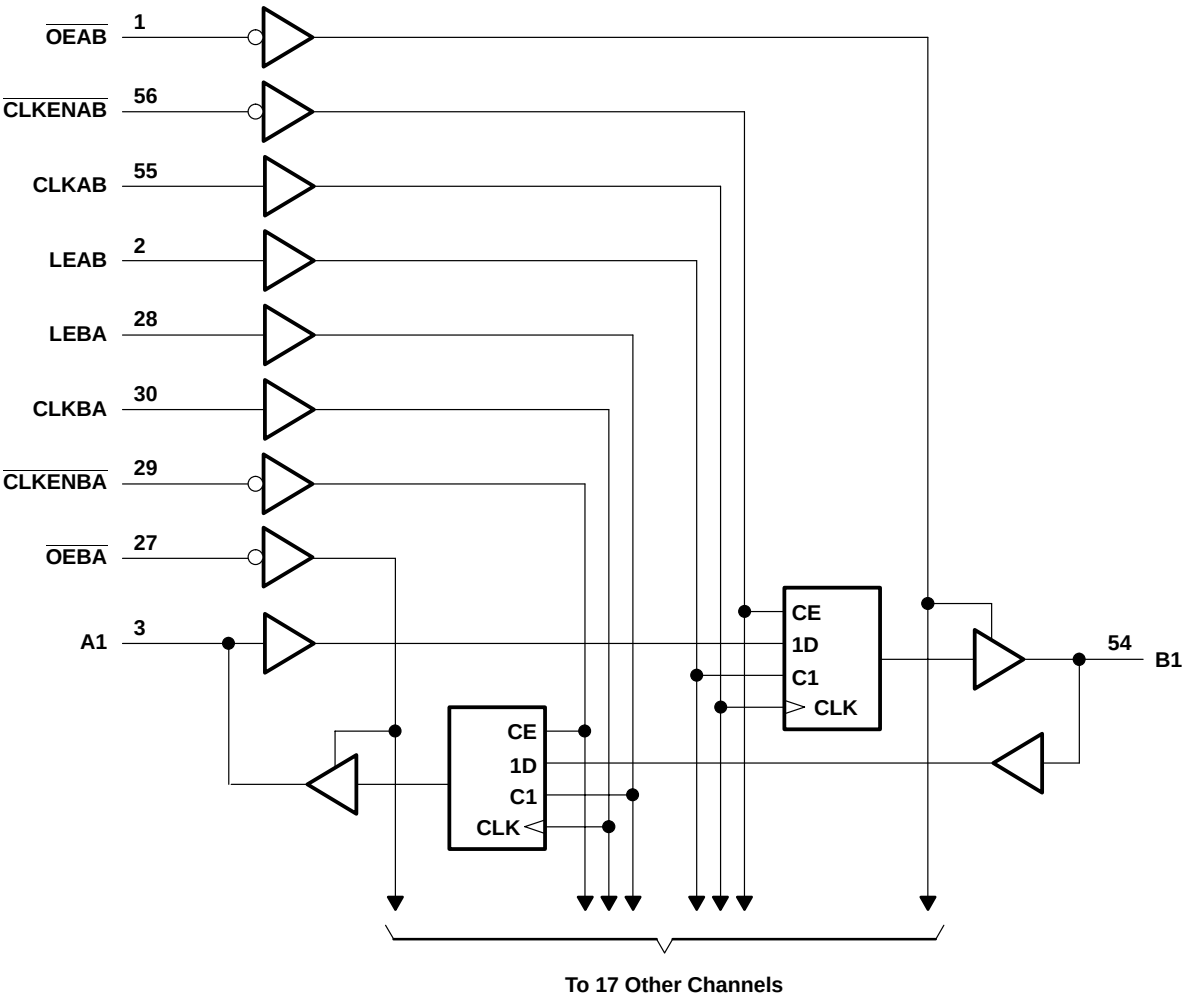
FUNCTION TABLE†

INPUTS					OUTPUT B
CLKENAB	OEAB	LEAB	CLKAB	A	
X	H	X	X	X	Z
X	L	H	X	L	L
X	L	H	X	H	H
H	L	L	X	X	B ₀ ‡
H	L	L	X	X	B ₀ ‡
L	L	L	↑	L	L
L	L	L	↑	H	H
L	L	L	L or H	X	B ₀ ‡

† A-to-B data flow is shown: B-to-A flow is similar but uses OEBA, LEBA, CLKBA, and CLKENBA.

‡ Output level before the indicated steady-state input conditions were established

logic diagram (positive logic)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
		I _{OL} = 12 mA	2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ} [§]		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	4			pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V	8			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.



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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

				V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT	
				MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
f _{clock}	Clock frequency			†		150		150		150		MHz	
t _w	Pulse duration	LE high		†		3.3		3.3		3.3		ns	
		CLK high or low		†		3.3		3.3		3.3			
t _{su}	Setup time	Data before CLK↑		†		2.3		2.4		2.1		ns	
		Data before LE↓	CLK high		†		2		1.6		1.6		
			CLK low		†		1.3		1.2		1.1		
		CLKEN before CLK↑		†		2		2		1.7			
t _h	Hold time	Data after CLK↑		†		0.7		0.7		0.8		ns	
		Data after LE↓	CLK high		†		1.3		1.6		1.4		
			CLK low		†		1.7		2		1.7		
		CLKEN after CLK↑		†		0.3		0.5		0.6			

† This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	A or B	B or A	†		1 4		4.6		4.1		ns
	LEAB or LEBA	A or B	†		1 4.6		5.3		4.7		
	CLKAB or CLKBA		†		1.2 5.2		5.8		5		
t _{en}	OEAB or OEBA	A or B	†		1.1 5.3		6.1		5.2		ns
t _{dis}	OEAB or OEBA	A or B	†		1.4 4.9		4.8		4.4		ns

† This information was not available at the time of publication.

operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER			TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
				TYP	TYP	TYP	
C_{pd}	Power dissipation capacitance	Outputs enabled	$C_L = 50\text{ pF}, f = 10\text{ MHz}$	†	41	52	pF
		Outputs disabled		†	6	6	

† This information was not available at the time of publication.



SN74ALVCH16601

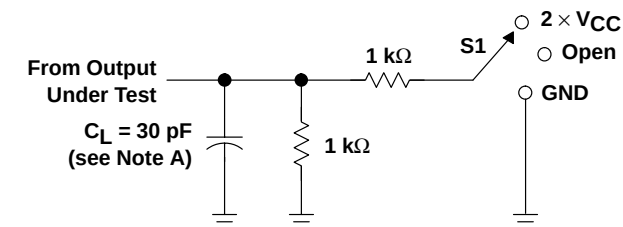
18-BIT UNIVERSAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

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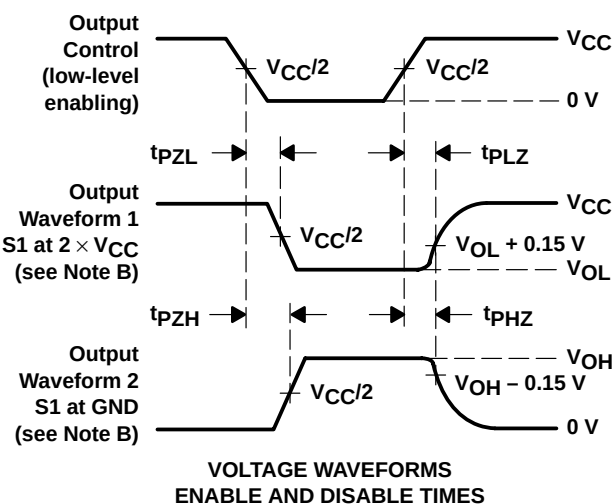
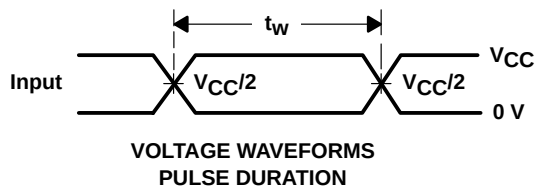
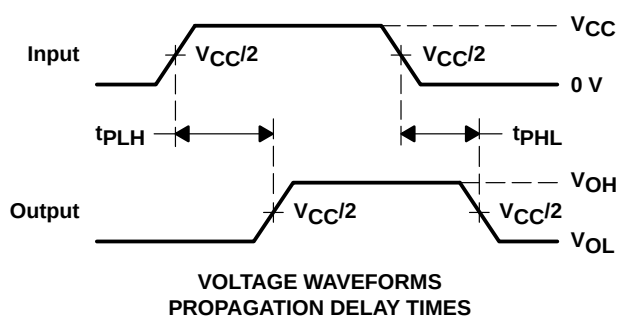
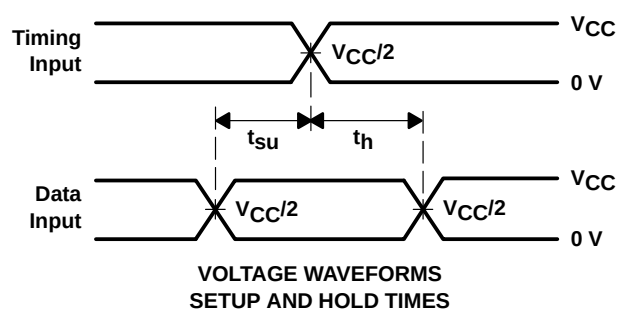
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times$ V_{CC}
t_{PHZ}/t_{PHL}	GND

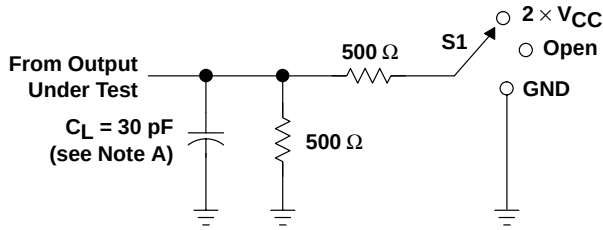


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

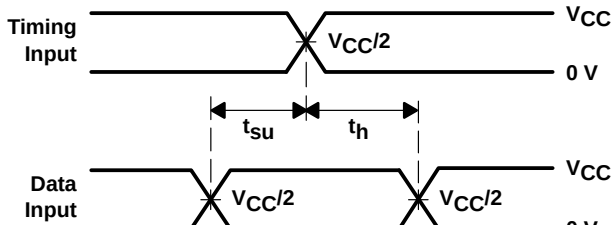
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

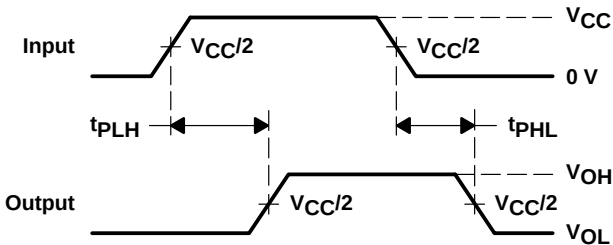


LOAD CIRCUIT

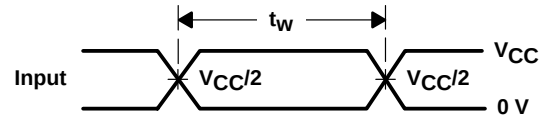
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



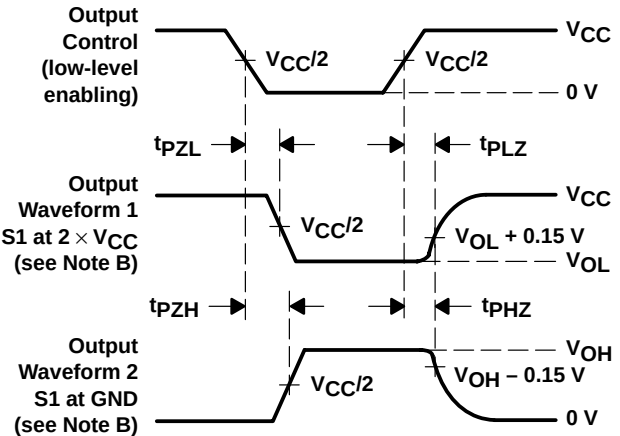
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH16601

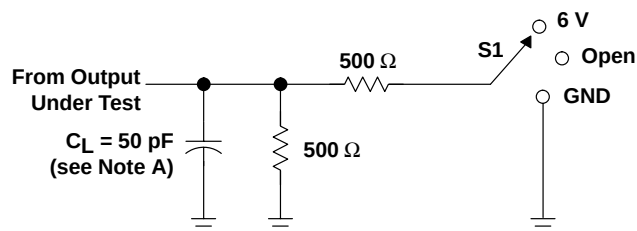
18-BIT UNIVERSAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

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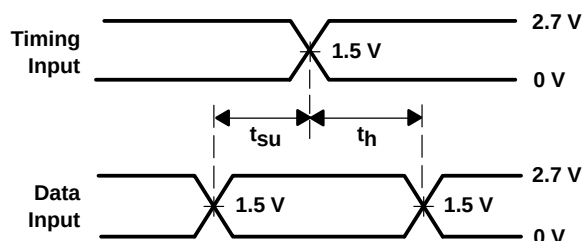
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$

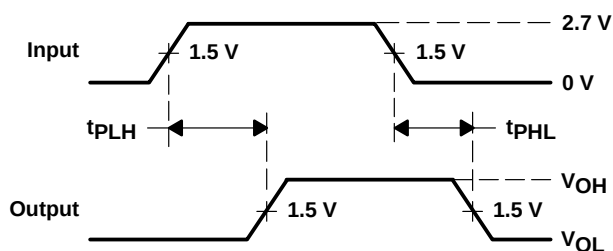


LOAD CIRCUIT

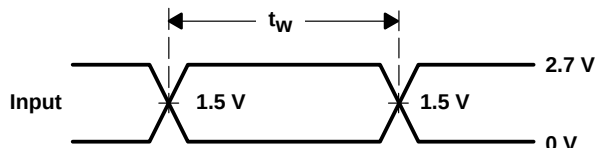
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



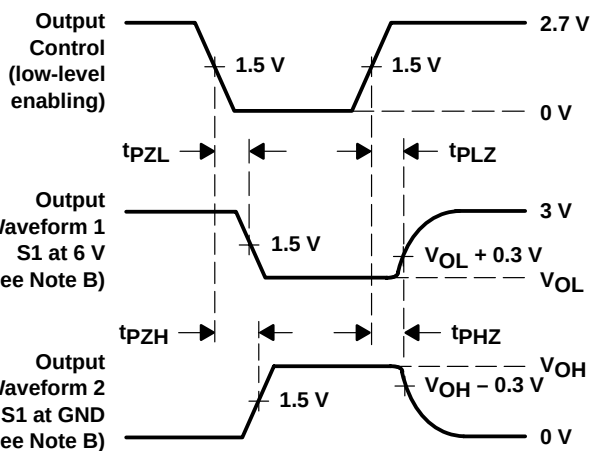
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

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16-BIT BUS TRANSCEIVER AND REGISTER WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages

description

This 16-bit bus transceiver and register is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16646 can be used as two 8-bit transceivers or one 16-bit transceiver. Data on the A or B bus is clocked into the registers on the low-to-high transition of the appropriate clock (CLKAB or CLKBA) input. Figure 1 illustrates the four fundamental bus-management functions that can be performed with the SN74ALVCH16646.

Output-enable ($\overline{OE}$) and direction-control (DIR) inputs are provided to control the transceiver functions. In the transceiver mode, data present at the high-impedance port may be stored in either register or in both. The select-control (SAB and SBA) inputs can multiplex stored and real-time (transparent mode) data. The circuitry used for select control eliminates the typical decoding glitch that occurs in a multiplexer during the transition between stored and real-time data. DIR determines which bus receives data when $\overline{OE}$ is low. In the isolation mode ($\overline{OE}$ high), A data may be stored in one register and/or B data may be stored in the other register.

When an output function is disabled, the input function is still enabled and may be used to store and transmit data. Only one of the two buses, A or B, can be driven at a time.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16646 is characterized for operation from -40°C to 85°C .

DGG, DGV, OR DL PACKAGE
(TOP VIEW)

1DIR	1	56	$1\overline{OE}$
1CLKAB	2	55	1CLKBA
1SAB	3	54	1SBA
GND	4	53	GND
1A1	5	52	1B1
1A2	6	51	1B2
V_{CC}	7	50	V_{CC}
1A3	8	49	1B3
1A4	9	48	1B4
1A5	10	47	1B5
GND	11	46	GND
1A6	12	45	1B6
1A7	13	44	1B7
1A8	14	43	1B8
2A1	15	42	2B1
2A2	16	41	2B2
2A3	17	40	2B3
GND	18	39	GND
2A4	19	38	2B4
2A5	20	37	2B5
2A6	21	36	2B6
V_{CC}	22	35	V_{CC}
2A7	23	34	2B7
2A8	24	33	2B8
GND	25	32	GND
2SAB	26	31	2SBA
2CLKAB	27	30	2CLKBA
2DIR	28	29	$2\overline{OE}$

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FUNCTION TABLE

INPUTS						DATA I/Os		OPERATION OR FUNCTION
OE	DIR	CLKAB	CLKBA	SAB	SBA	A1–A8	B1–B8	
X	X	↑	X	X	X	Input	Unspecified [†]	Store A, B unspecified [†]
X	X	X	↑	X	X	Unspecified [†]	Input	Store B, A unspecified [†]
H	X	↑	↑	X	X	Input	Input	Store A and B data
H	X	H or L	H or L	X	X	Input disabled	Input disabled	Isolation, hold storage
L	L	X	X	X	L	Output	Input	Real-time B data to A bus
L	L	X	H or L	X	H	Output	Input	Stored B data to A bus
L	H	X	X	L	X	Input	Output	Real-time A data to B bus
L	H	H or L	X	H	X	Input	Output	Stored A data to B bus

[†] The data-output functions may be enabled or disabled by various signals at OE and DIR. Data-input functions always are enabled; i.e., data at the bus terminals is stored on every low-to-high transition of the clock inputs.

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WITH 3-STATE OUTPUTS

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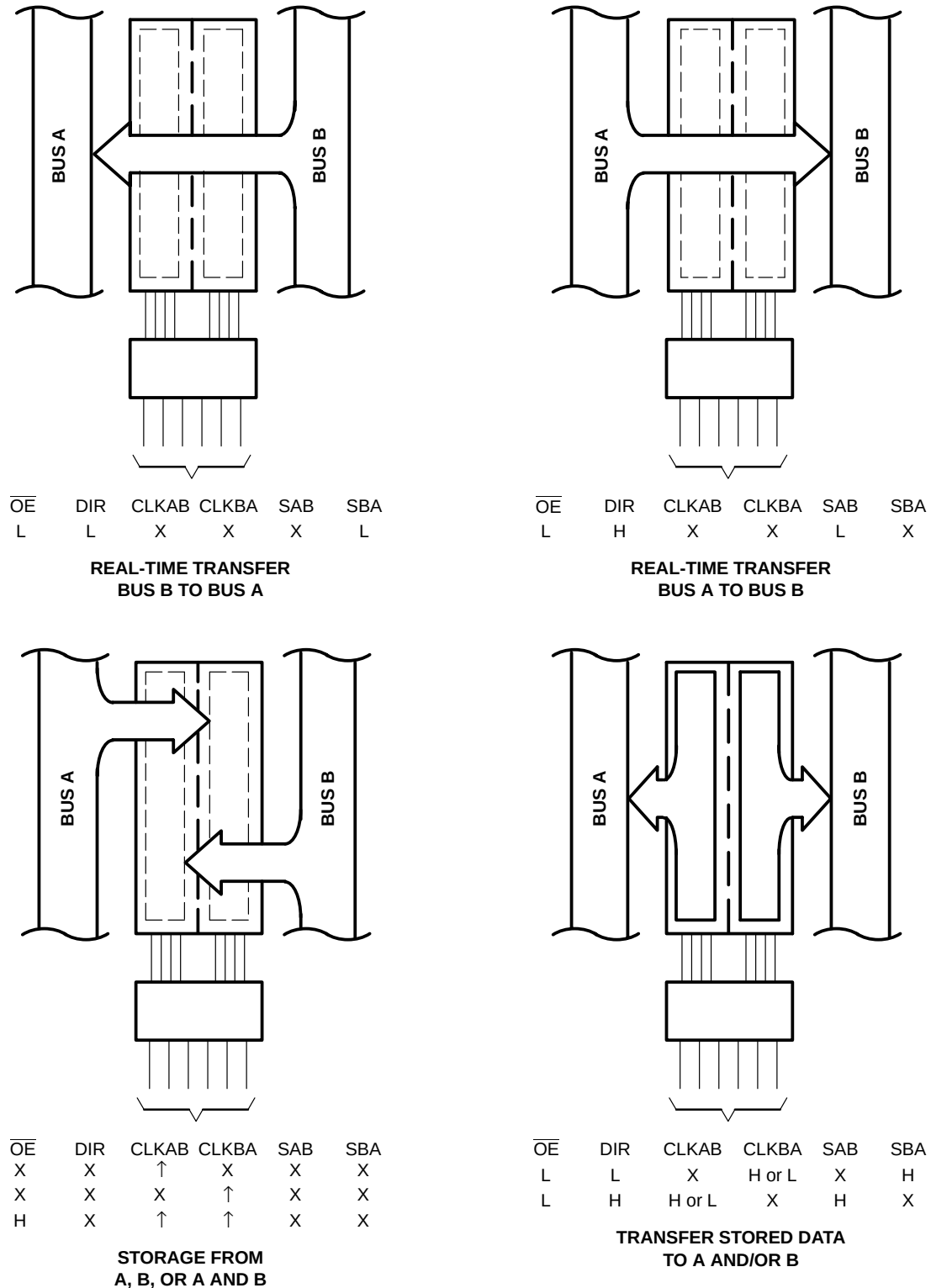


Figure 1. Bus-Management Functions

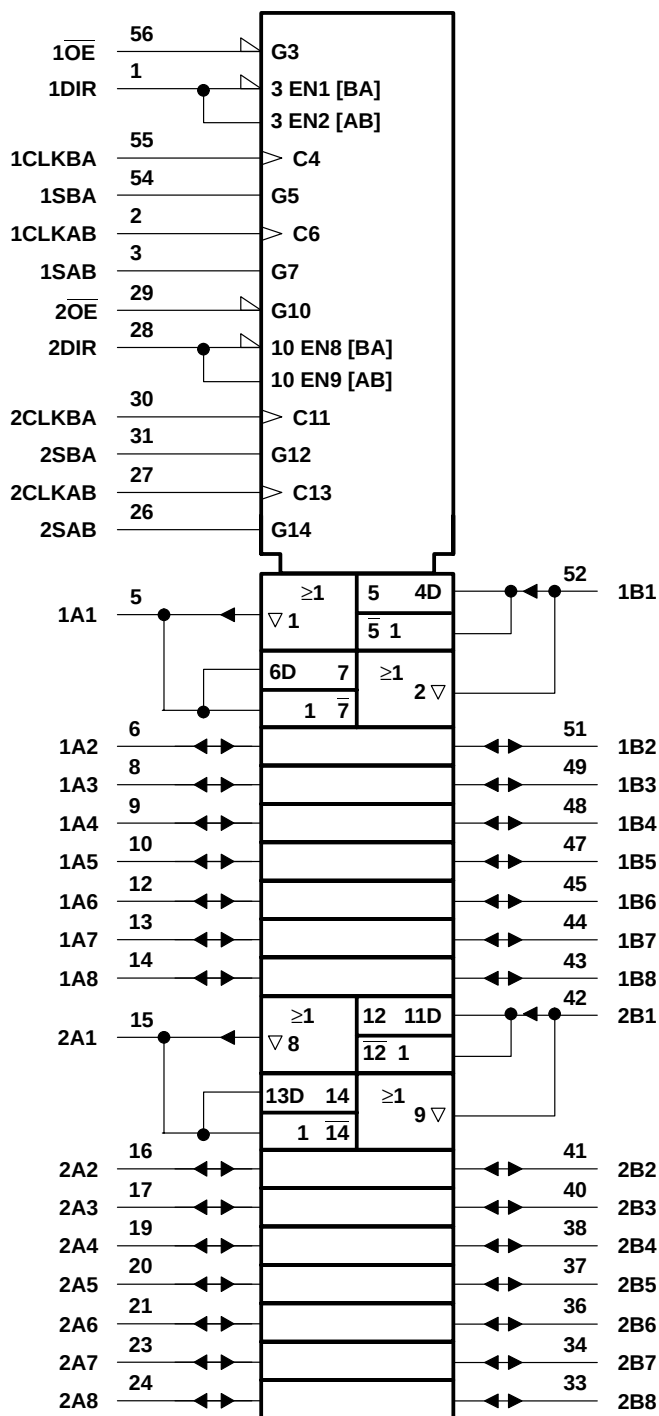
SN74ALVCH16646

16-BIT BUS TRANSCEIVER AND REGISTER

WITH 3-STATE OUTPUTS

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logic symbol†

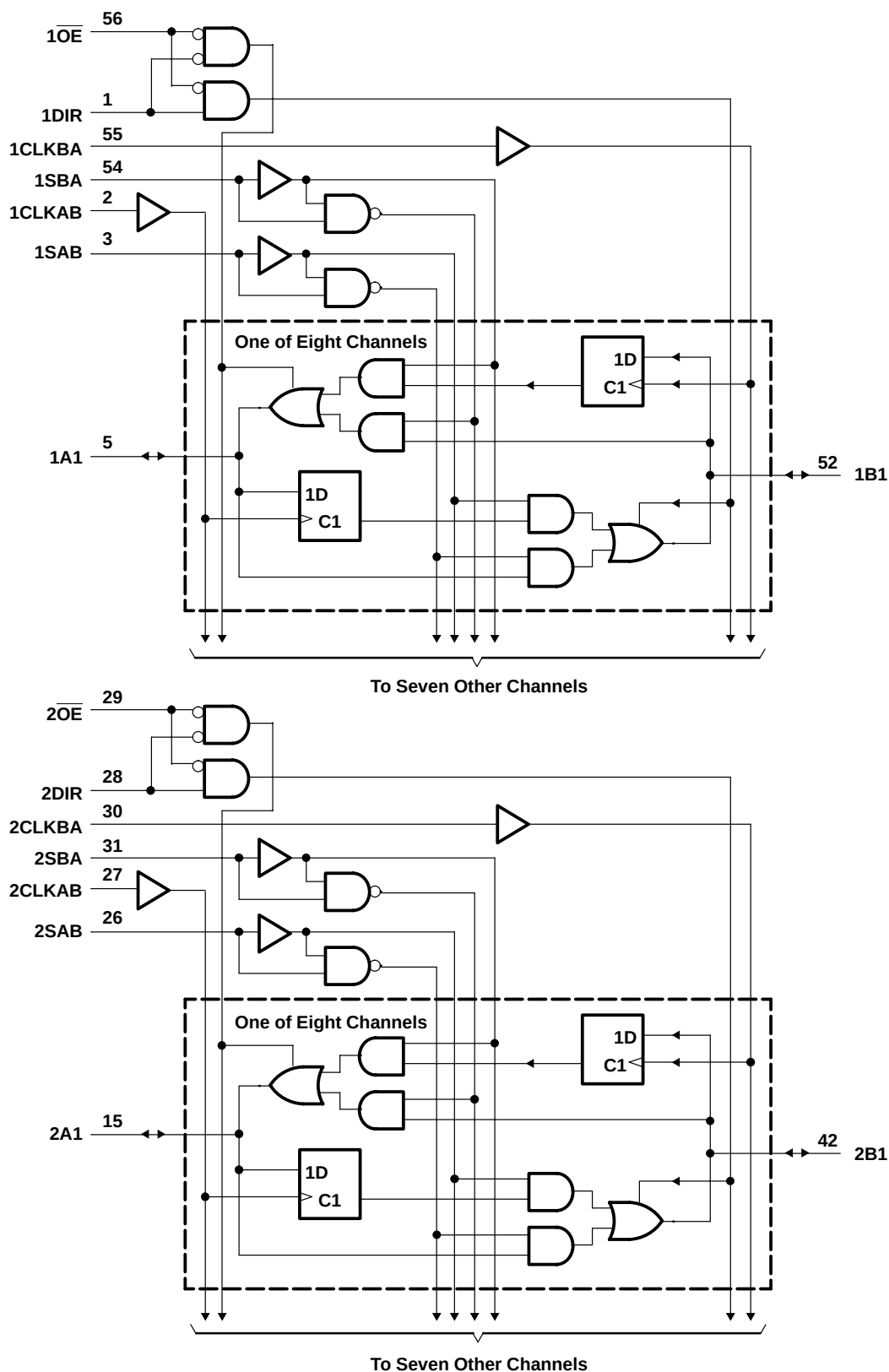


† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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16-BIT BUS TRANSCEIVER AND REGISTER
WITH 3-STATE OUTPUTS

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logic diagram (positive logic)



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16-BIT BUS TRANSCEIVER AND REGISTER WITH 3-STATE OUTPUTS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DGV package	86°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
		I _{OL} = 12 mA	2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ} [§]		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3.5			pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V	8.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 2 through 4)

			V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency		¶		150		150		150		MHz
t _w	Pulse duration	CLKAB or CLKBA high or low	¶		3.3		3.3		3.3		ns
t _{su}	Setup time	A before CLKAB↑ or B before CLKBA↑	¶		1.6		1.7		1.4		ns
t _h	Hold time	A after CLKAB↑ or B after CLKBA↑	¶		0.6		0.4		0.7		ns

¶ This information was not available at the time of publication.



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16-BIT BUS TRANSCEIVER AND REGISTER WITH 3-STATE OUTPUTS

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 2 through 4)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	A or B	B or A	†		1	4.8	4.5		1	3.9	ns
	CLKAB or CLKBA	A or B	†		1	5.6	5.2		1	4.5	
	SAB or SBA		†		1	6.8	6.4		1	5.3	
t _{en}	$\overline{OE}$	A or B	†		1	6.5	6.2		1	5.1	ns
t _{dis}	$\overline{OE}$	A or B	†		1.6	5.7	5		1.4	4.7	ns
t _{en}	DIR	A or B	†		1	7.8	6.2		1	5.1	ns
t _{dis}	DIR	A or B	†		1.5	6.5	6		1.1	5.3	ns

† This information was not available at the time of publication.

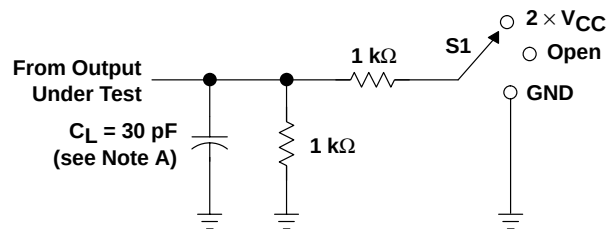
operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 50 pF, f = 10 MHz	†	39	43	pF
		Outputs disabled		†	10	12	

† This information was not available at the time of publication.

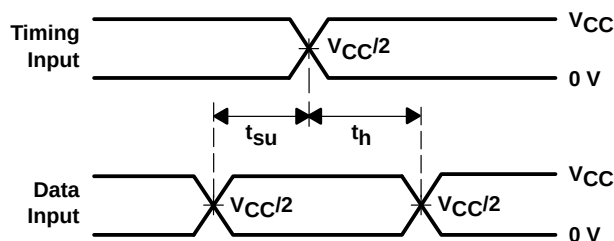
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$

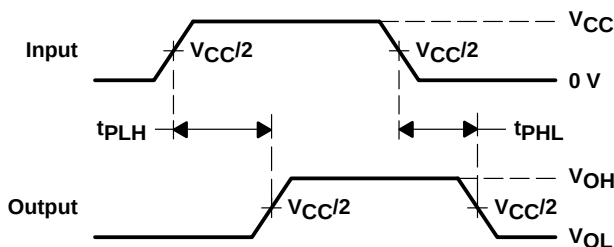


LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



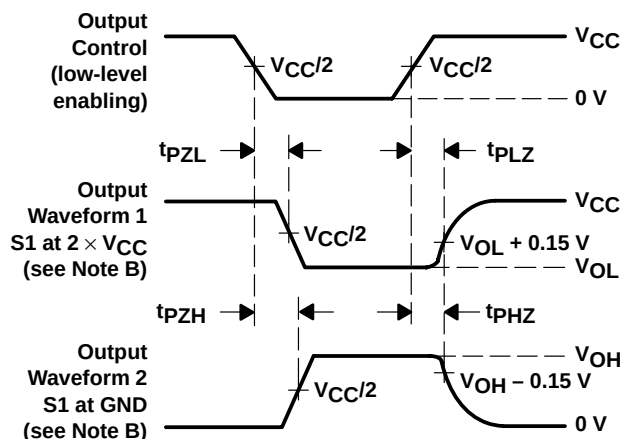
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH16646

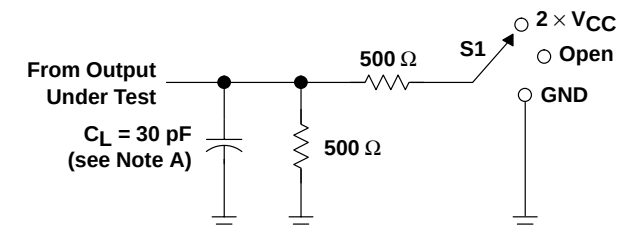
16-BIT BUS TRANSCEIVER AND REGISTER

WITH 3-STATE OUTPUTS

SCES032E– JULY 1995 – REVISED FEBRUARY 1999

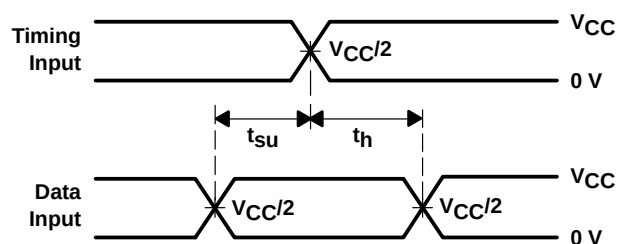
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

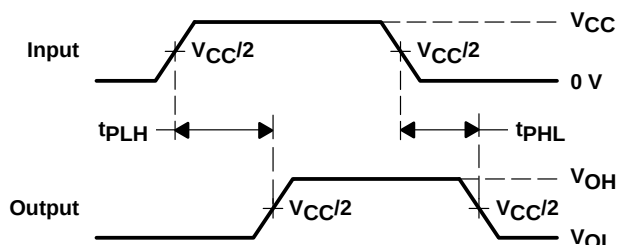


LOAD CIRCUIT

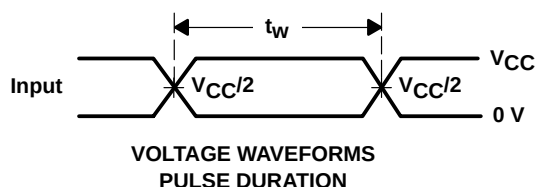
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



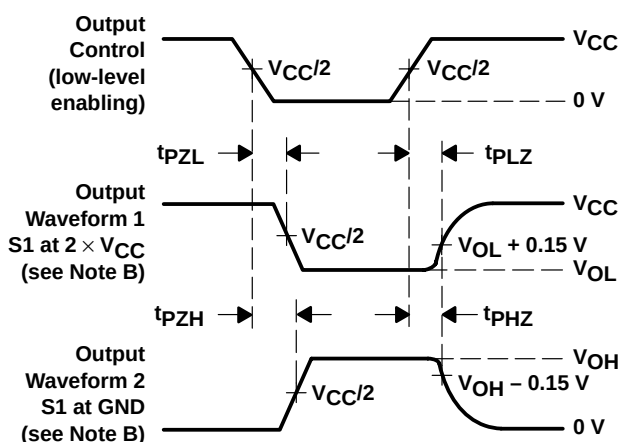
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



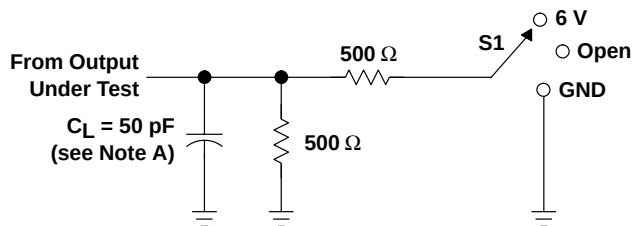
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

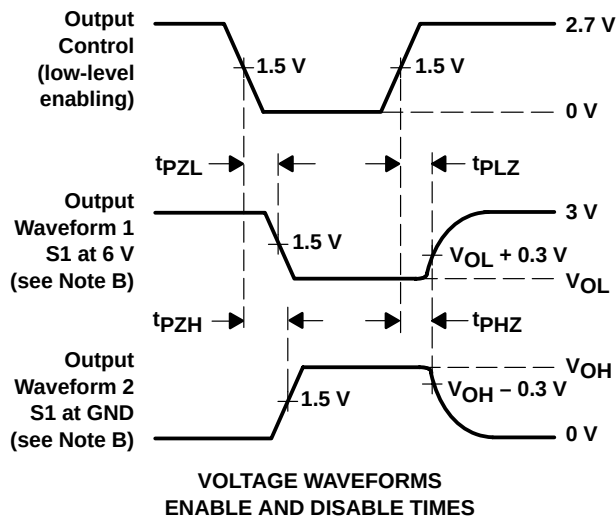
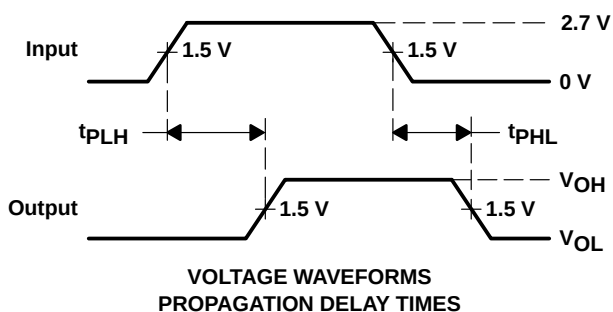
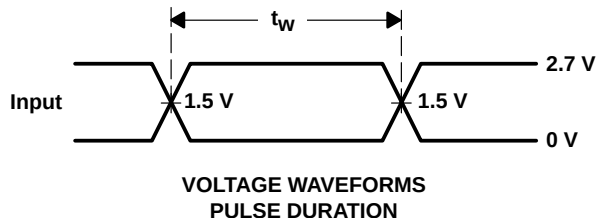
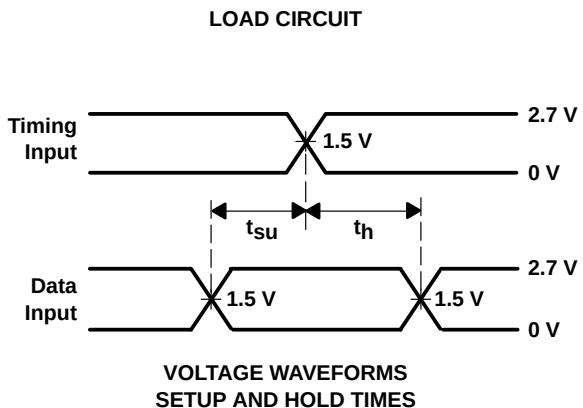
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 4. Load Circuit and Voltage Waveforms

SN74ALVCH16652 16-BIT BUS TRANSCEIVER AND REGISTER WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 16-bit bus transceiver and register is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16652 consists of D-type flip-flops and control circuitry arranged for multiplexed transmission of data directly from the data bus or from the internal storage registers. The device can be used as two 8-bit transceivers or one 16-bit transceiver.

Complementary output-enable (OEAB and $\overline{OEBA}$) inputs are provided to control the transceiver functions. Select-control (SAB and SBA) inputs are provided to select whether real-time or stored data is transferred. A low input level selects real-time data, and a high input level selects stored data. The circuitry used for select control eliminates the typical decoding glitch that occurs in a multiplexer during the transition between stored and real-time data. Figure 1 illustrates the four fundamental bus-management functions that can be performed with the SN74ALVCH16652.

Data on the A or B bus, or both, can be stored in the internal D flip-flops by low-to-high transitions at the appropriate clock (CLKAB or CLKBA) inputs regardless of the levels on the select-control or output-enable inputs. When SAB and SBA are in the real-time transfer mode, it also is possible to store data without using the internal D-type flip-flops by simultaneously enabling OEAB and $\overline{OEBA}$. In this configuration, each output reinforces its input. Thus, when all other data sources to the two sets of bus line are in the high-impedance state, each set of bus lines remains at its last level configuration.

Active bus-hold circuitry is provided to hold unused for floating inputs at a valid logic level.

To ensure the high-impedance state during power up or power down, $\overline{OEBA}$ should be tied to V_{CC} through a pullup resistor and OEAB should be tied to GND through a pulldown resistor; the minimum value of the resistor is determined by the current-sinking current-sourcing capability of the driver.

The SN74ALVCH16652 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)

1OEAB	1	56	$\overline{1OEBA}$
1CLKAB	2	55	1CLKBA
1SAB	3	54	1SBA
GND	4	53	GND
1A1	5	52	1B1
1A2	6	51	1B2
V_{CC}	7	50	V_{CC}
1A3	8	49	1B3
1A4	9	48	1B4
1A5	10	47	1B5
GND	11	46	GND
1A6	12	45	1B6
1A7	13	44	1B7
1A8	14	43	1B8
2A1	15	42	2B1
2A2	16	41	2B2
2A3	17	40	2B3
GND	18	39	GND
2A4	19	38	2B4
2A5	20	37	2B5
2A6	21	36	2B6
V_{CC}	22	35	V_{CC}
2A7	23	34	2B7
2A8	24	33	2B8
GND	25	32	GND
2SAB	26	31	2SBA
2CLKAB	27	30	2CLKBA
2OEAB	28	29	$\overline{2OEBA}$

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FUNCTION TABLE

INPUTS						DATA I/O [†]		OPERATION OR FUNCTION
OEAB	OEBA	CLKAB	CLKBA	SAB	SBA	A1–A8	B1–B8	
L	H	H or L	H or L	X	X	Input	Input	Isolation
L	H	↑	↑	X	X	Input	Input	Store A and B data
X	H	↑	H or L	X	X	Input	Unspecified [‡]	Store A, hold B
H	H	↑	↑	X [‡]	X	Input	Output	Store A in both registers
L	X	H or L	↑	X	X	Unspecified [‡]	Input	Hold A, store B
L	L	↑	↑	X	X [‡]	Output	Input	Store B in both registers
L	L	X	X	X	L	Output	Input	Real-time B data to A bus
L	L	X	H or L	X	H	Output	Input	Stored B data to A bus
H	H	X	X	L	X	Input	Output	Real-time A data to B bus
H	H	H or L	X	H	X	Input	Output	Stored A data to B bus
H	L	H or L	H or L	H	H	Output	Output	Stored A data to B bus and stored B data to A bus

[†] The data output functions may be enabled or disabled by a variety of level combinations at the OEAB or OEBA inputs. Data input functions are always enabled; i.e., data at the bus pins is stored on every low-to-high transition of the clock inputs.

[‡] Select control = L; clocks can occur simultaneously
Select control = H; clocks must be staggered in order to load both registers

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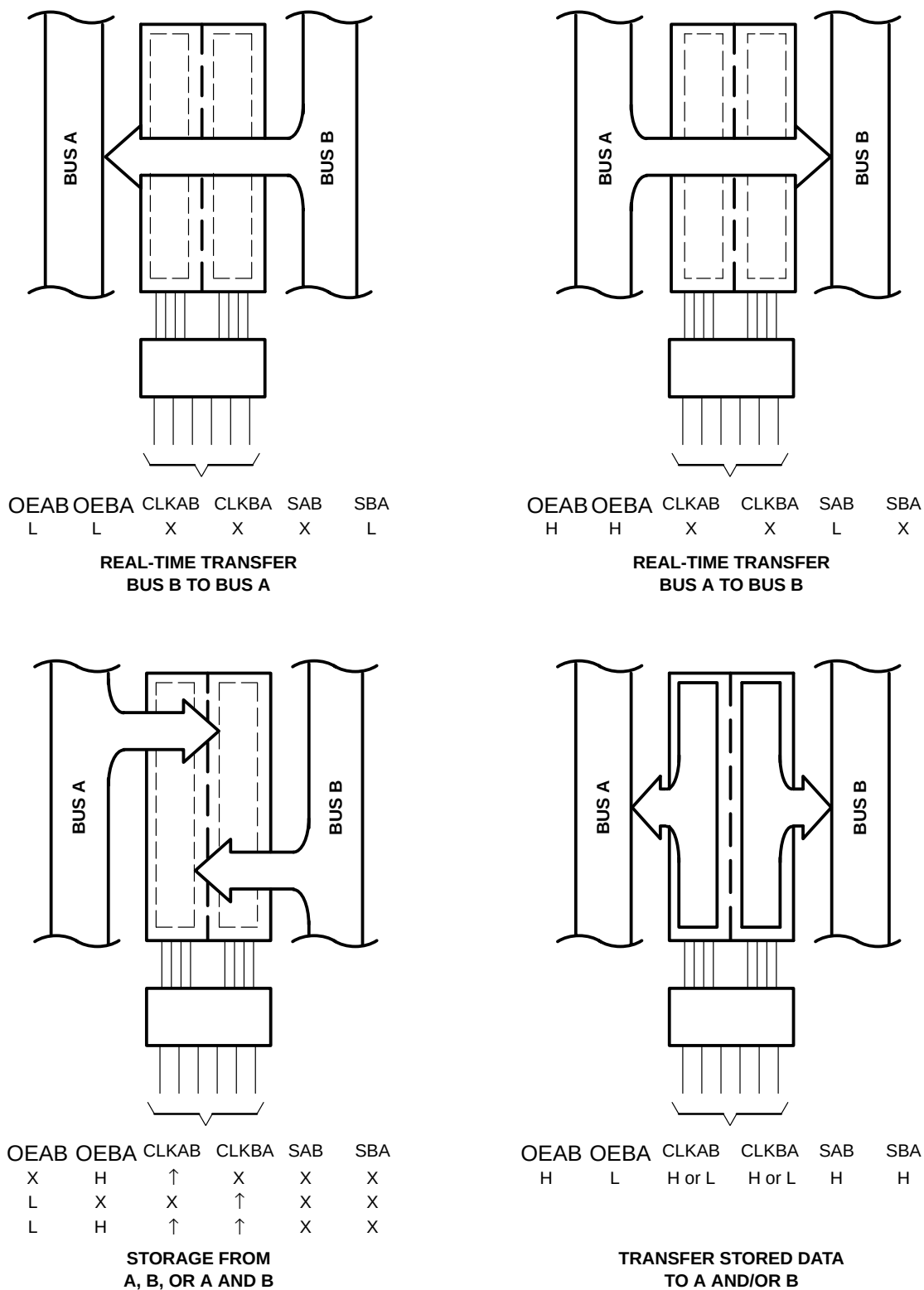
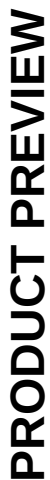


Figure 1. Bus-Management Functions

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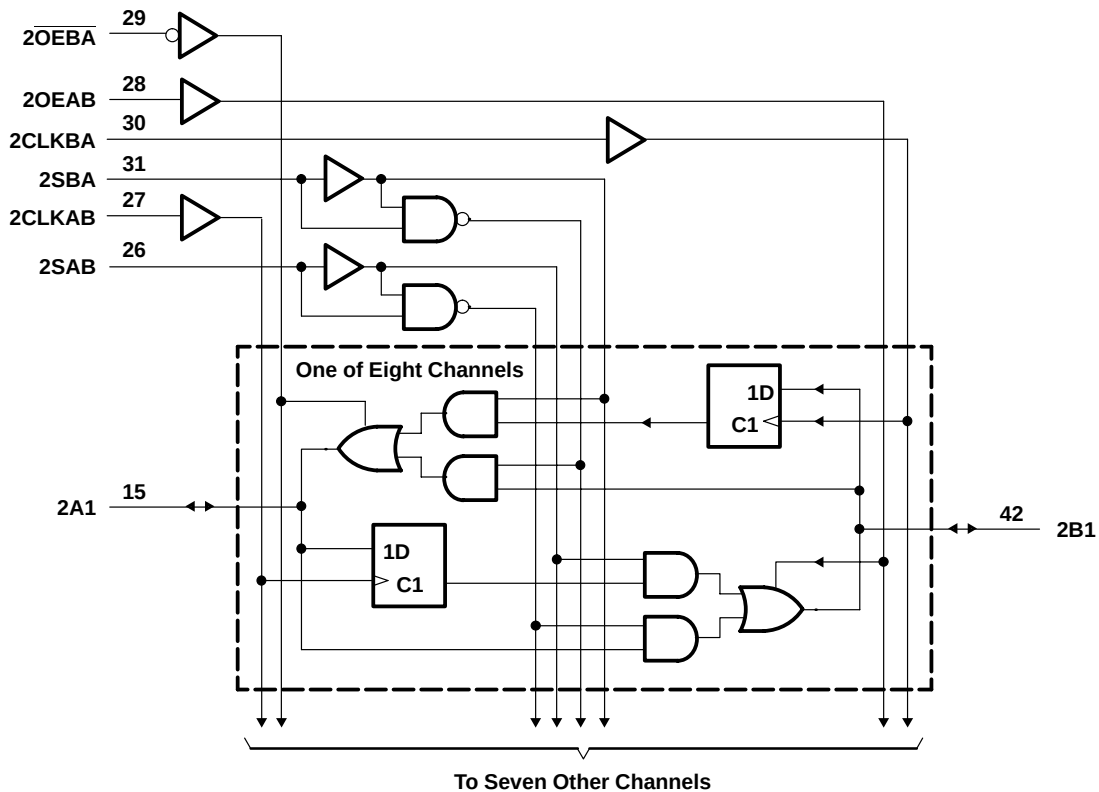
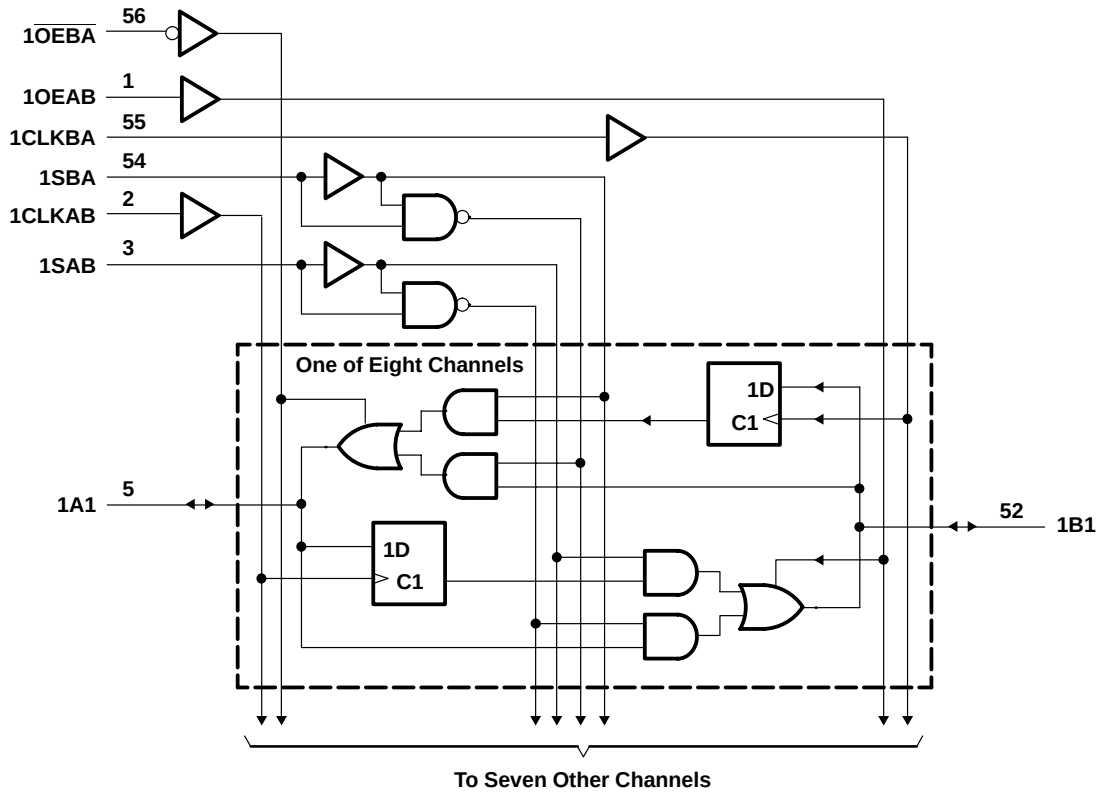
100



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logic diagram (positive logic)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output-voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V			±5	µA
I _{I(hold)}	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V			±500	
I _{OZ} [§]	V _O = V _{CC} or GND	3.6 V			±10	µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V			40	µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V			750	µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V			pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 2 through 4)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency									MHz
t _w	Pulse duration, CLK high or low									ns
t _{su}	Setup time, A or B before CLKAB↑ or CLKBA↑									ns
t _h	Hold time, A or B after CLKAB↑ or CLKBA↑									ns

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 2 through 4)

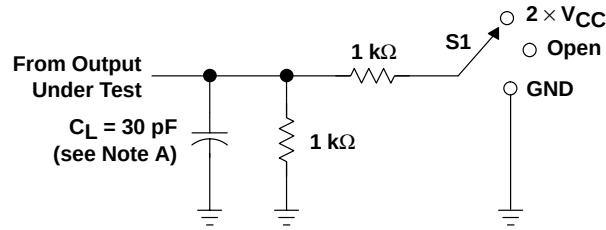
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}											MHz
t _{pd}	A or B	B or A									ns
	CLKAB or CLKBA	A or B									
	SAB or SBA	B or A									
t _{en}	OE or OE	A or B									ns
t _{dis}	OE or OE	A or B									ns

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance per transceiver	Outputs enabled	f = 10 MHz				pF
		Outputs disabled					

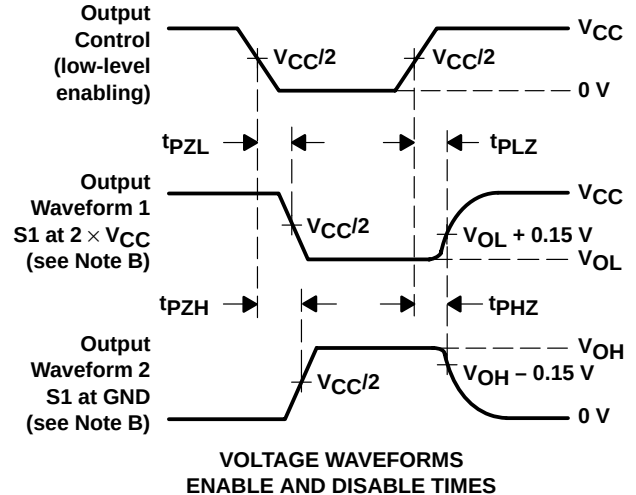
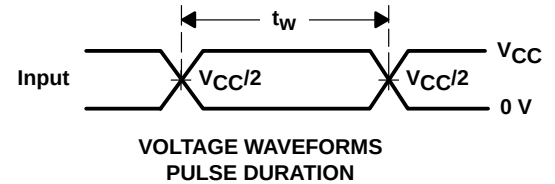
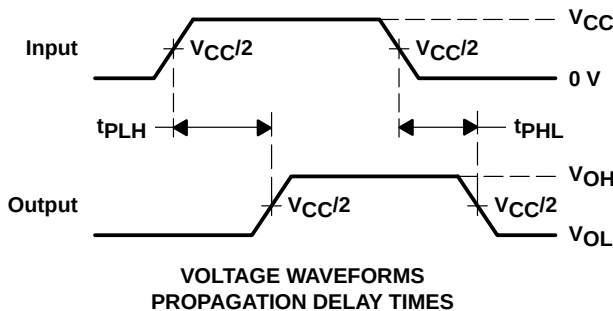
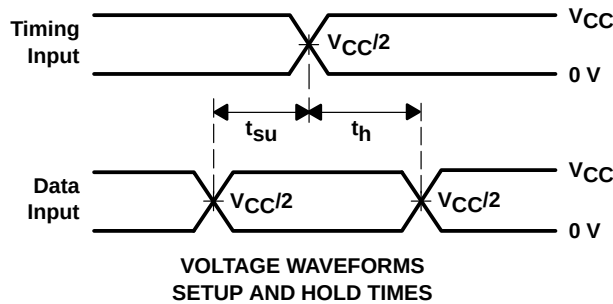
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PHZ}	GND



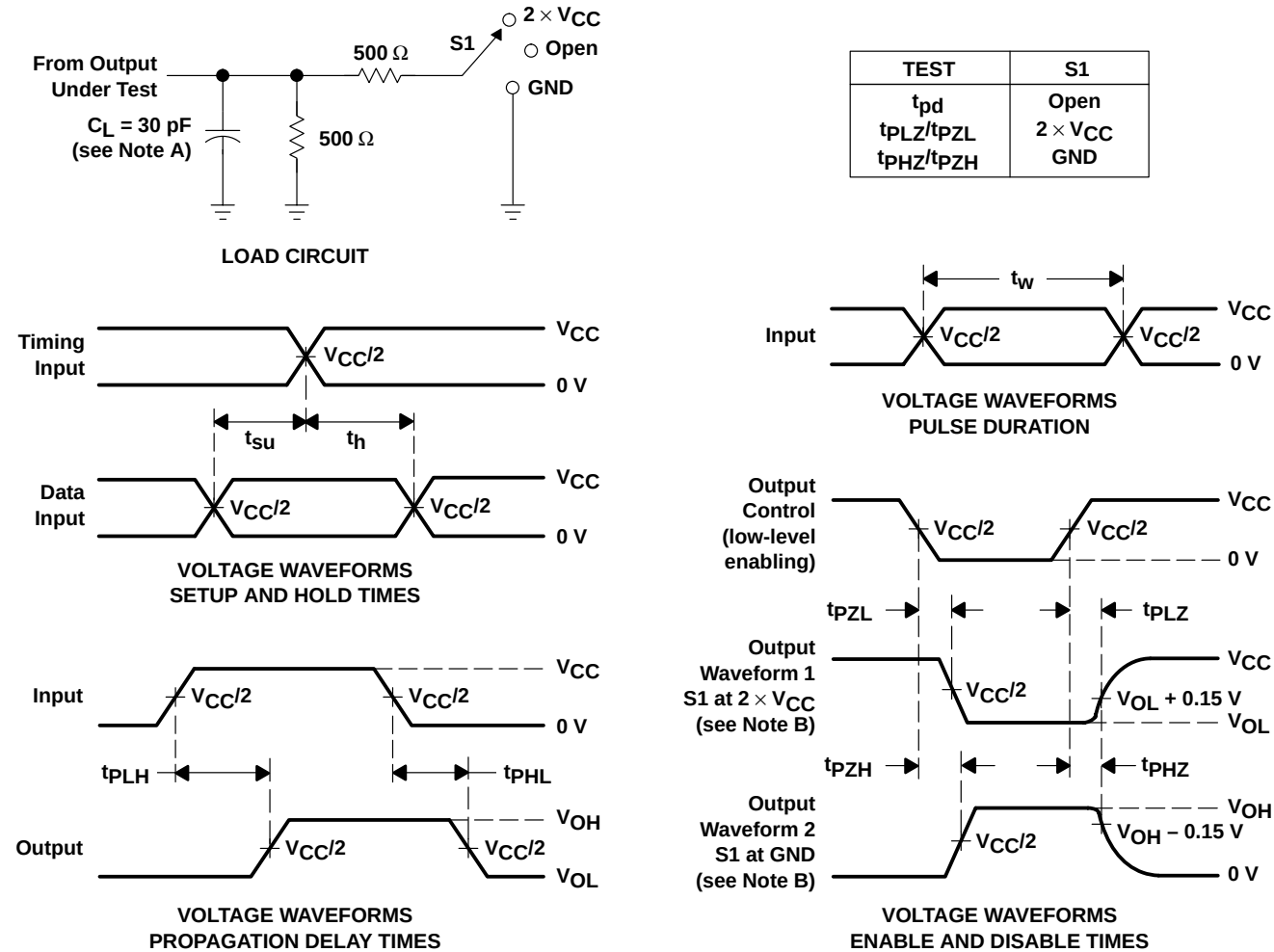
- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH16652 16-BIT BUS TRANSCEIVER AND REGISTER WITH 3-STATE OUTPUTS

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PARAMETER MEASUREMENT INFORMATION $V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$

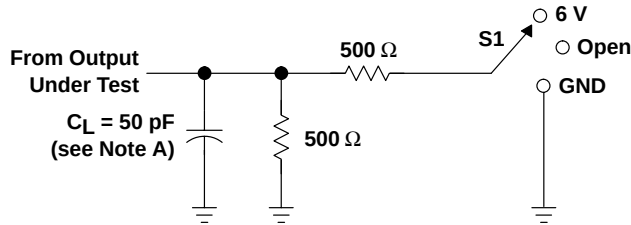


- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

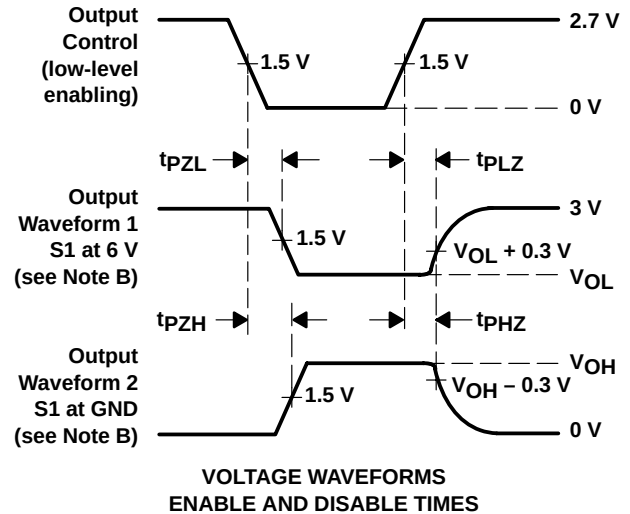
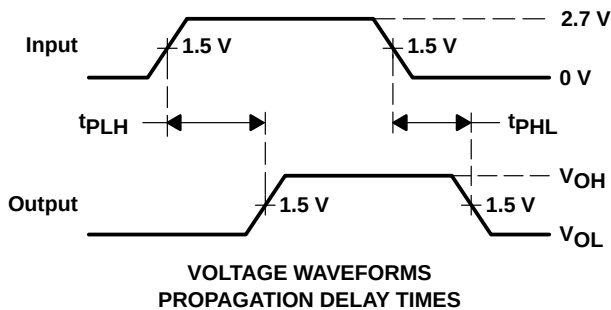
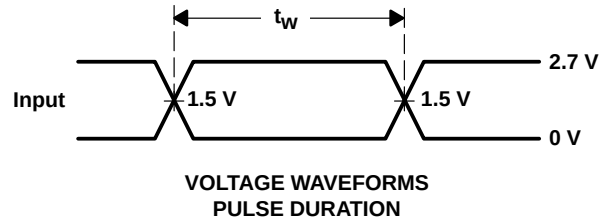
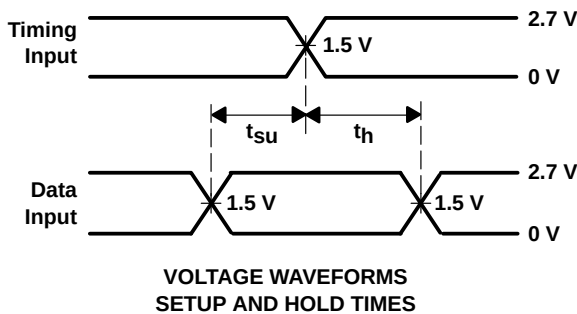
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dLZ} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 4. Load Circuit and Voltage Waveforms

SN74ALVCH16721

3.3-V 20-BIT FLIP-FLOP WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages

description

This 20-bit flip-flop is designed specifically for 1.65-V to 3.6-V V_{CC} operation.

The 20 flip-flops of the SN74ALVCH16721 are edge-triggered D-type flip-flops with qualified clock storage. On the positive transition of the clock (CLK) input, the device provides true data at the Q outputs if the clock-enable ($\overline{CLKEN}$) input is low. If $\overline{CLKEN}$ is high, no data is stored.

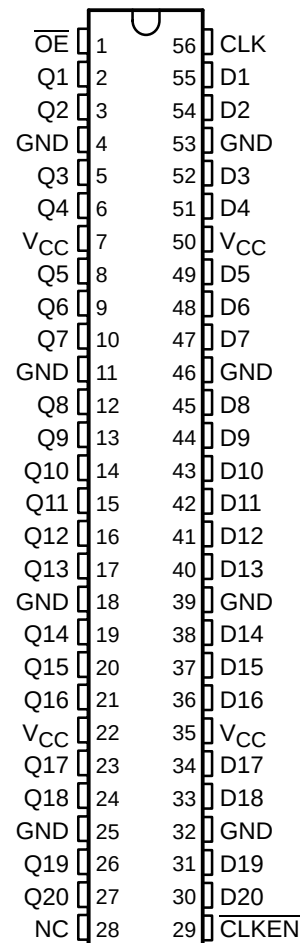
A buffered output-enable ($\overline{OE}$) input places the 20 outputs in either a normal logic state (high or low) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without need for interface or pullup components. $\overline{OE}$ does not affect the internal operation of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16721 is characterized for operation from -40°C to 85°C .

DGG, DGV, OR DL PACKAGE (TOP VIEW)



NC – No internal connection

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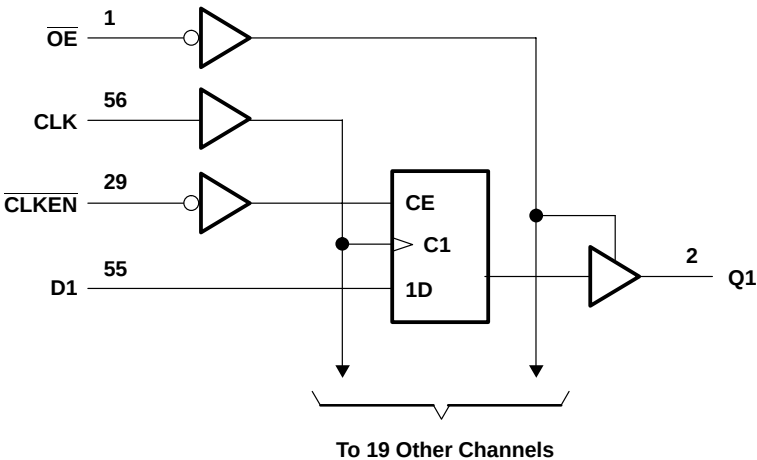
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FUNCTION TABLE

(each flip-flop)

INPUTS				OUTPUT
$\overline{OE}$	$\overline{CLKEN}$	CLK	D	Q
L	H	X	X	Q_0
L	L	$\uparrow$	H	H
L	L	$\uparrow$	L	L
L	L	L or H	X	Q_0
H	X	X	X	Z

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}		–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)		–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)		–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)		–50 mA
Output clamp current, I_{OK} ($V_O < 0$)		–50 mA
Continuous output current, I_O		± 50 mA
Continuous current through each V_{CC} or GND		± 100 mA
Package thermal impedance, θ_{JA} (see Note 3):	DGG package	81°C/W
	DGV package	86°C/W
	DL package	74°C/W
Storage temperature range, T_{stg}		–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

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WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate			10	ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



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3.3-V 20-BIT FLIP-FLOP
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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	3.3 V	3.5			pF
	Data inputs		6			
C _O	Outputs	3.3 V	7			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency		§		150		150		150		MHz
t _w	Pulse duration, CLK high or low		§		3.3		3.3		3.3		ns
t _{su}	Setup time	Data before CLK↑	§		4		3.6		3.1		ns
		CLKEN before CLK↑	§		3.4		3.1		2.7		
t _h	Hold time	Data after CLK↑	§		0		0		0		ns
		CLKEN after CLK↑	§		0		0		0		

§ This information was not available at the time of publication.



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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	CLK	Q	†		1	5.6	1	5.1	1	4.3	ns
t _{en}	$\overline{OE}$	Q	†		1	6.1	1	5.8	1	4.8	ns
t _{dis}	$\overline{OE}$	Q	†		1	5.5	1	4.7	1	4.4	ns

† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 50 pF, f = 10 MHz	†	55	59	pF
		Outputs disabled		†	46	49	

† This information was not available at the time of publication.



SN74ALVCH16721

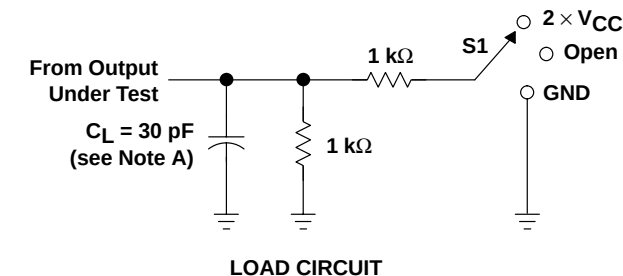
3.3-V 20-BIT FLIP-FLOP

WITH 3-STATE OUTPUTS

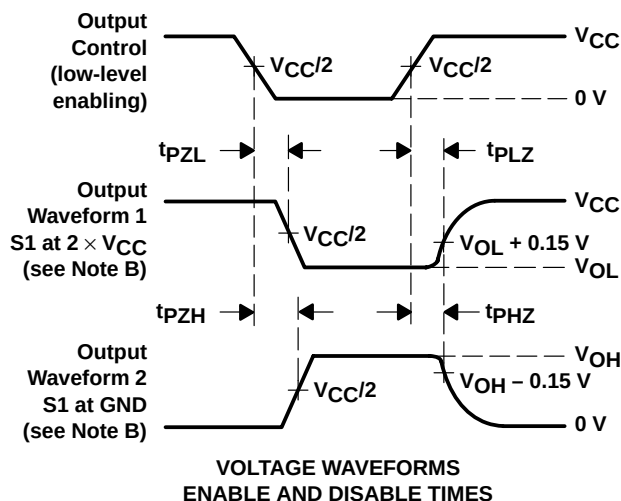
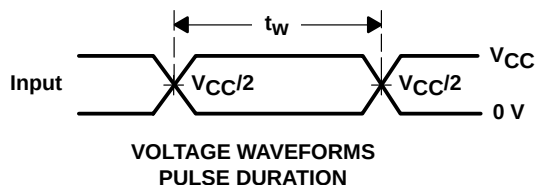
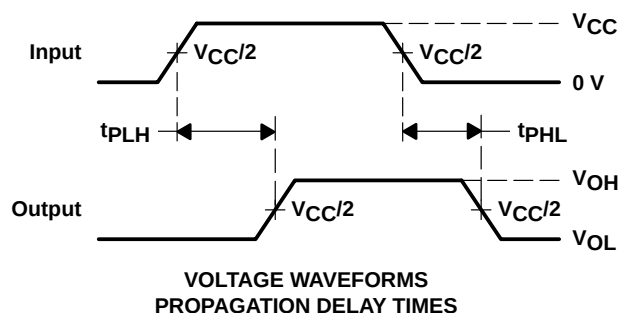
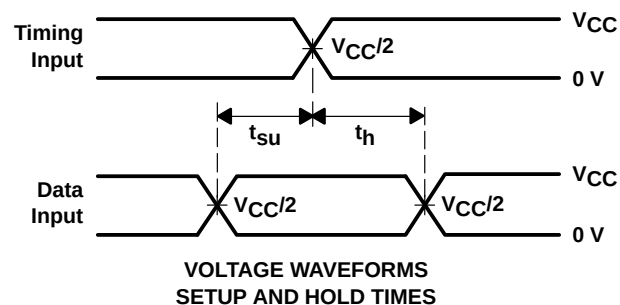
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PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND

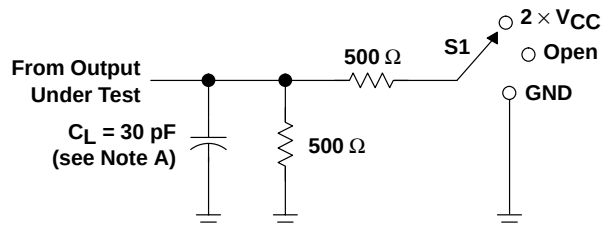


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

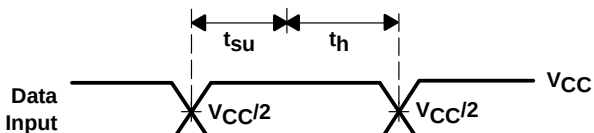
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

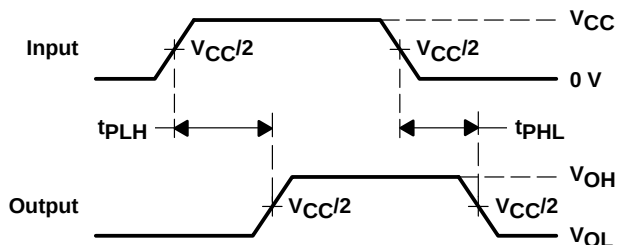


LOAD CIRCUIT

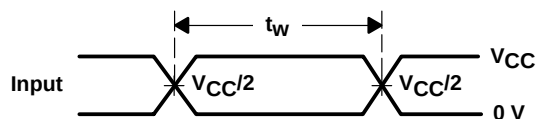
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times$ V_{CC}
t_{PHZ}/t_{PZH}	GND



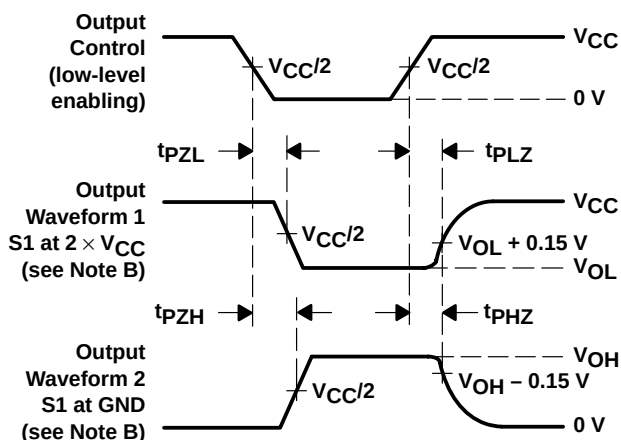
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH16721

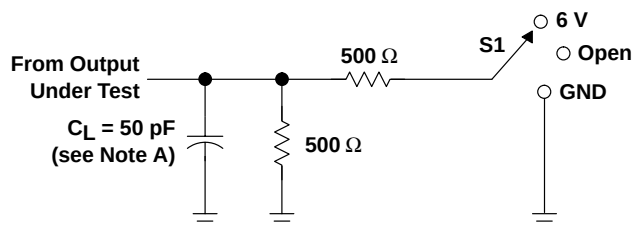
3.3-V 20-BIT FLIP-FLOP

WITH 3-STATE OUTPUTS

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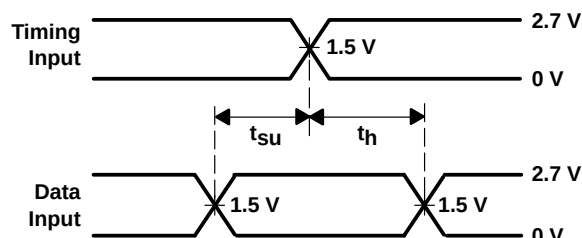
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$

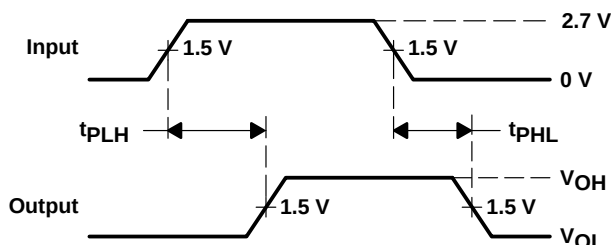


LOAD CIRCUIT

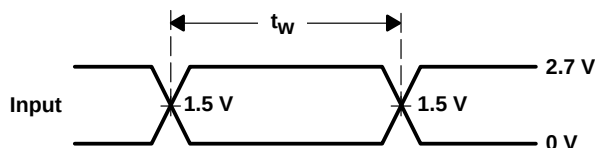
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



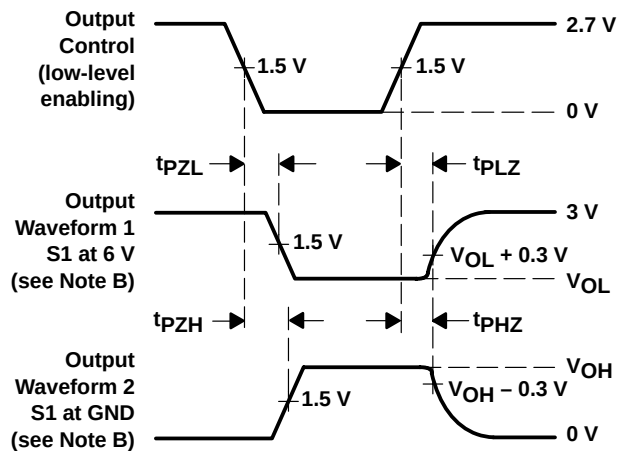
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16820

3.3-V 10-BIT FLIP-FLOP WITH DUAL OUTPUTS AND 3-STATE OUTPUTS

SCES035E – JULY 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 10-bit flip-flop is designed for 1.65-V to 3.6-V V_{CC} operation.

The flip-flops of the SN74ALVCH16820 are edge-triggered D-type flip-flops. On the positive transition of the clock (CLK) input, the device provides true data at the Q outputs.

A buffered output-enable ($\overline{OE}$) input can be used to place the ten outputs in either a normal logic state (high or low logic level) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without need for interface or pullup components.

$\overline{OE}$ input does not affect the internal operation of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16820 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE (TOP VIEW)

$1\overline{OE}$	1	56	CLK
1Q1	2	55	D1
1Q2	3	54	NC
GND	4	53	GND
2Q1	5	52	D2
2Q2	6	51	NC
V_{CC}	7	50	V_{CC}
3Q1	8	49	D3
3Q2	9	48	NC
4Q1	10	47	D4
GND	11	46	GND
4Q2	12	45	NC
5Q1	13	44	D5
5Q2	14	43	NC
6Q1	15	42	D6
6Q2	16	41	NC
7Q1	17	40	D7
GND	18	39	GND
7Q2	19	38	NC
8Q1	20	37	D8
8Q2	21	36	NC
V_{CC}	22	35	V_{CC}
9Q1	23	34	D9
9Q2	24	33	NC
GND	25	32	GND
10Q1	26	31	D10
10Q2	27	30	NC
$2\overline{OE}$	28	29	NC

NC – No internal connection

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SN74ALVCH16820
3.3-V 10-BIT FLIP-FLOP WITH DUAL OUTPUTS
AND 3-STATE OUTPUTS

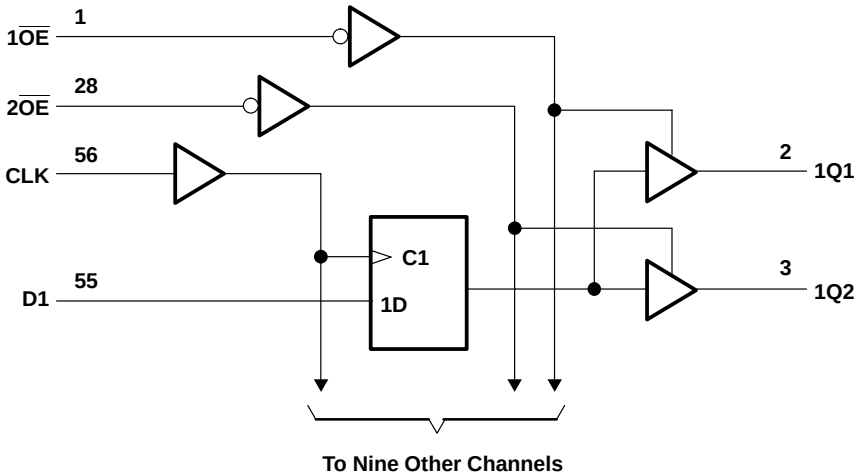
SCES035E – JULY 1995 – REVISED FEBRUARY 1999

FUNCTION TABLE
(each flip-flop)

INPUTS			OUTPUT
$\overline{OE}_n^\dagger$	CLK	D	$Q_n^\dagger$
L	↑	H	H
L	↑	L	L
L	L	X	Q_0
H	X	X	Z

$^\dagger n = 1, 2$

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[‡]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[‡] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.



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3.3-V 10-BIT FLIP-FLOP WITH DUAL OUTPUTS
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recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate			10	ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	3.3 V	3.5			pF
	Data inputs		6			
C _O	Outputs	3.3 V	7			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency	§		150		150		150		MHz
t _w	Pulse duration, CLK high or low	§		3.3		3.3		3.3		ns
t _{su}	Setup time, data before CLK↑	§		1.7		1.8		1.4		ns
t _h	Hold time, data after CLK↑	§		1.1		1.1		1		ns

[§] This information was not available at the time of publication.


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3.3-V 10-BIT FLIP-FLOP WITH DUAL OUTPUTS
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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	CLK	Q	†		1	5.9	5.5		1	4.8	ns
t _{en}	$\overline{\text{OE}}$	Q	†		1	6.4	6.1		1	5	ns
t _{dis}	$\overline{\text{OE}}$	Q	†		1	5.7	5		1	4.5	ns

† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	All outputs enabled	C _L = 50 pF, f = 10 MHz	†	60	63	pF
		All outputs disabled		†	38	46	

† This information was not available at the time of publication.



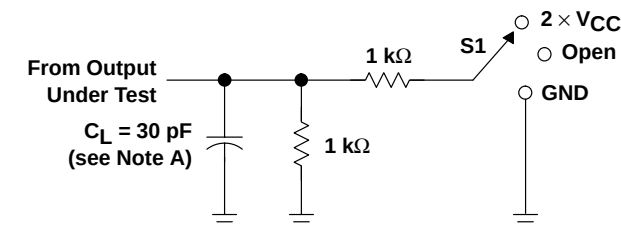
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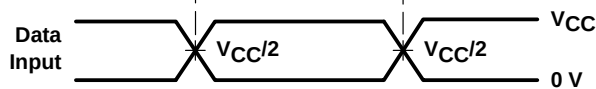
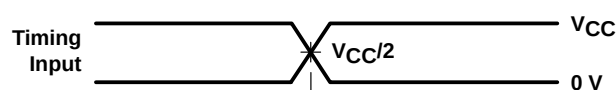
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8\text{ V}$

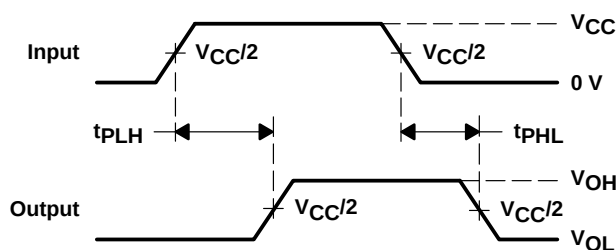


LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PHZ}	GND



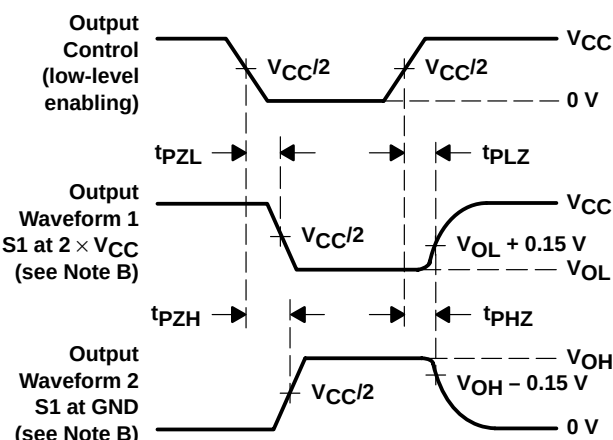
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

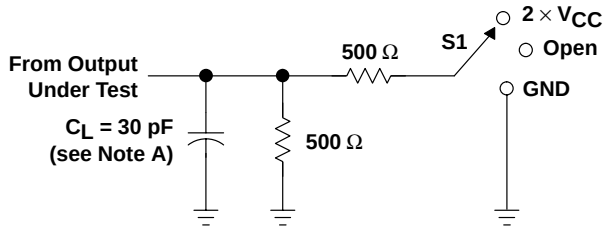
Figure 1. Load Circuit and Voltage Waveforms

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3.3-V 10-BIT FLIP-FLOP WITH DUAL OUTPUTS
AND 3-STATE OUTPUTS

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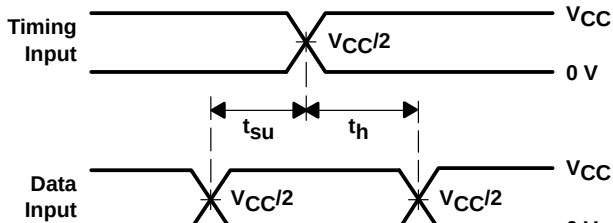
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$

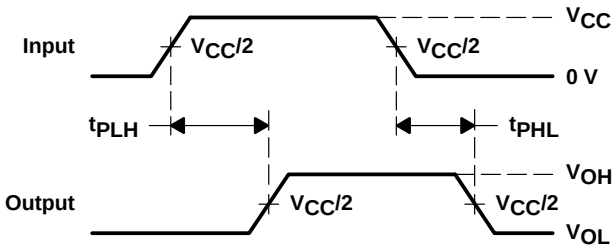


LOAD CIRCUIT

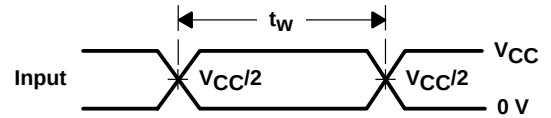
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	$2 \times V_{CC}$
t_{PHZ}/t_{PZH}	GND



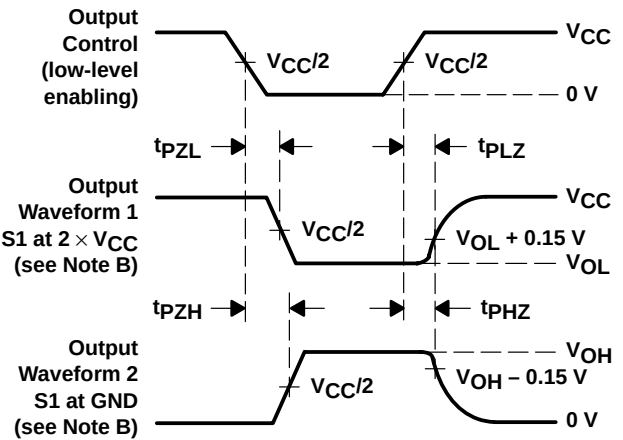
**VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES**



**VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES**



**VOLTAGE WAVEFORMS
PULSE DURATION**



**VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES**

- NOTES: A. C_L includes probe and jig capacitance.
 B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 D. The outputs are measured one at a time with one transition per measurement.
 E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 F. t_{PZL} and t_{PZH} are the same as t_{en} .
 G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

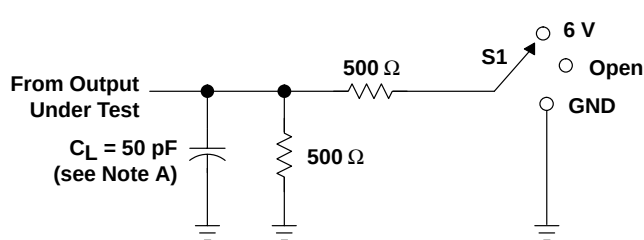
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3.3-V 10-BIT FLIP-FLOP WITH DUAL OUTPUTS AND 3-STATE OUTPUTS

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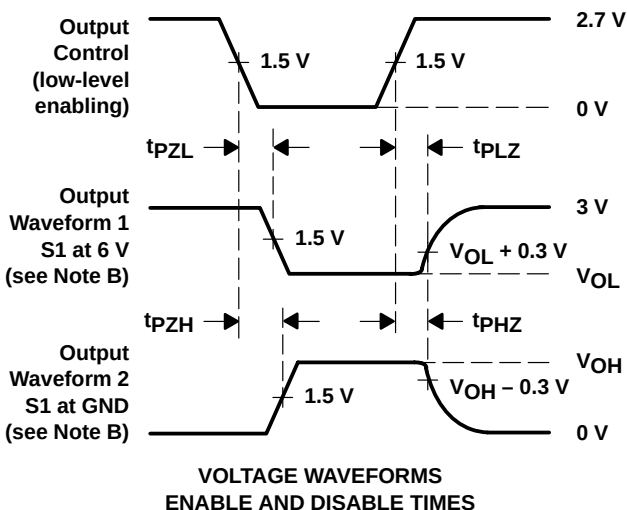
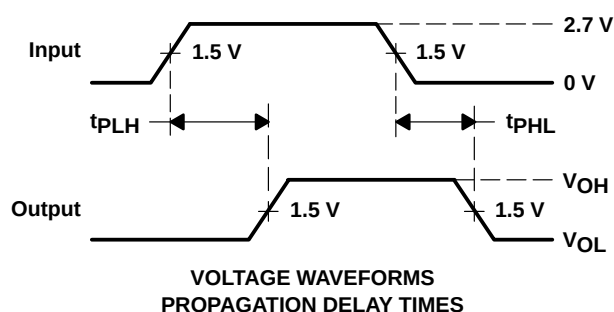
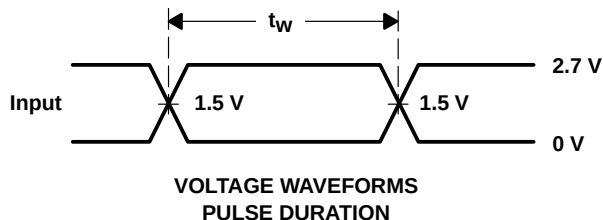
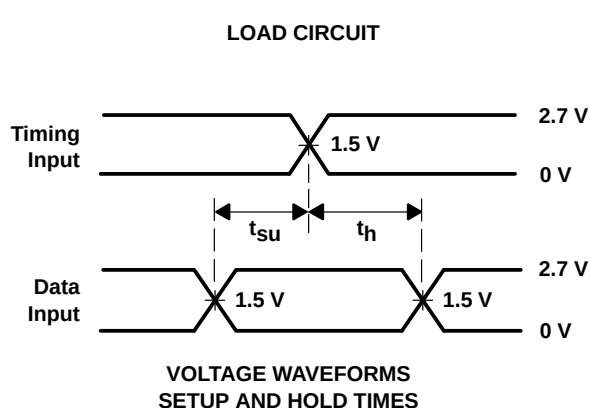
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: PRR $\leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

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3.3-V 20-BIT BUS-INTERFACE FLIP-FLOP WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 20-bit bus-interface flip-flop is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16821 can be used as two 10-bit flip-flops or one 20-bit flip-flop. The 20 flip-flops are edge-triggered D-type flip-flops. On the positive transition of the clock (CLK) input, the device provides true data at the Q outputs.

A buffered output-enable ($\overline{OE}$) input can be used to place the ten outputs in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without need for interface or pullup components.

$\overline{OE}$ does not affect the internal operation of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16821 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)

$1\overline{OE}$	1	56	1CLK
1Q1	2	55	1D1
1Q2	3	54	1D2
GND	4	53	GND
1Q3	5	52	1D3
1Q4	6	51	1D4
V_{CC}	7	50	V_{CC}
1Q5	8	49	1D5
1Q6	9	48	1D6
1Q7	10	47	1D7
GND	11	46	GND
1Q8	12	45	1D8
1Q9	13	44	1D9
1Q10	14	43	1D10
2Q1	15	42	2D1
2Q2	16	41	2D2
2Q3	17	40	2D3
GND	18	39	GND
2Q4	19	38	2D4
2Q5	20	37	2D5
2Q6	21	36	2D6
V_{CC}	22	35	V_{CC}
2Q7	23	34	2D7
2Q8	24	33	2D8
GND	25	32	GND
2Q9	26	31	2D9
2Q10	27	30	2D10
$2\overline{OE}$	28	29	2CLK

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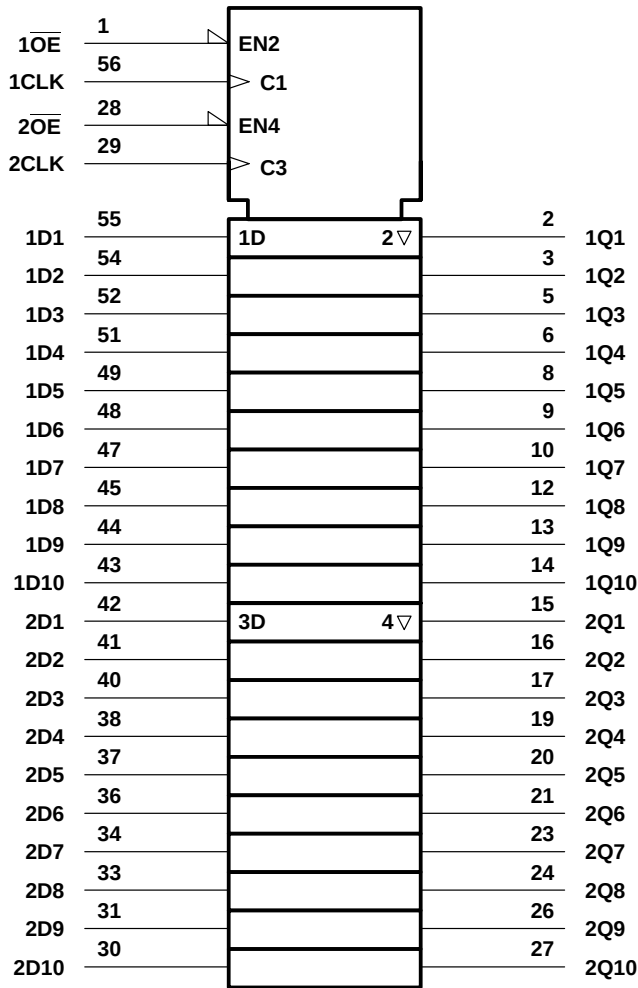
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3.3-V 20-BIT BUS-INTERFACE FLIP-FLOP
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FUNCTION TABLE
(each 10-bit flip-flop)

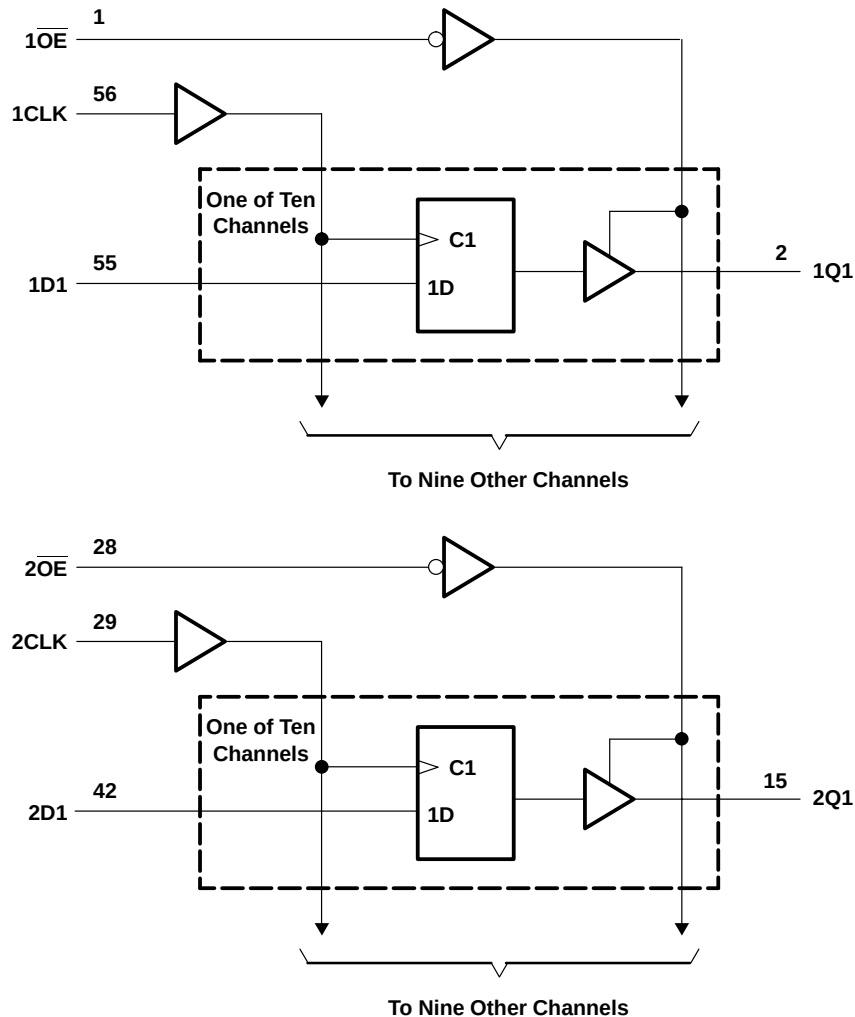
INPUTS			OUTPUT Q
$\overline{\text{OE}}$	CLK	D	
L	$\uparrow$	H	H
L	$\uparrow$	L	L
L	H or L	X	Q_0
H	X	X	Z

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65\text{ V to }1.95\text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3\text{ V to }2.7\text{ V}$	1.7	
		$V_{CC} = 2.7\text{ V to }3.6\text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65\text{ V to }1.95\text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3\text{ V to }2.7\text{ V}$	0.7	
		$V_{CC} = 2.7\text{ V to }3.6\text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65\text{ V}$	–4	mA
		$V_{CC} = 2.3\text{ V}$	–12	
		$V_{CC} = 2.7\text{ V}$	–12	
		$V_{CC} = 3\text{ V}$	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65\text{ V}$	4	mA
		$V_{CC} = 2.3\text{ V}$	12	
		$V_{CC} = 2.7\text{ V}$	12	
		$V_{CC} = 3\text{ V}$	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V		3.5	pF
	Data inputs				6	
C _O	Outputs	V _O = V _{CC} or GND	3.3 V		7	pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency	§		150		150		150		MHz
t _w	Pulse duration, CLK high or low	§		3.3		3.3		3.3		ns
t _{su}	Setup time, data before CLK↑	§		4.4		3.9		3.4		ns
t _h	Hold time, data after CLK↑	§		0		0		0		ns

§ This information was not available at the time of publication.



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WITH 3-STATE OUTPUTS

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	CLK	Q		†	1	5.8	5.3		1	4.5	ns
t _{en}	$\overline{OE}$	Q		†	1	6.6	6.2		1	5.1	ns
t _{dis}	$\overline{OE}$	Q		†	1	5.7	5		1	4.6	ns

† This information was not available at the time of publication.

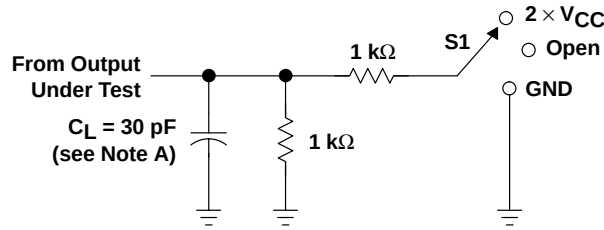
operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 50 pF, f = 10 MHz	†	36	40	pF
		Outputs disabled		†	22	24	

† This information was not available at the time of publication.

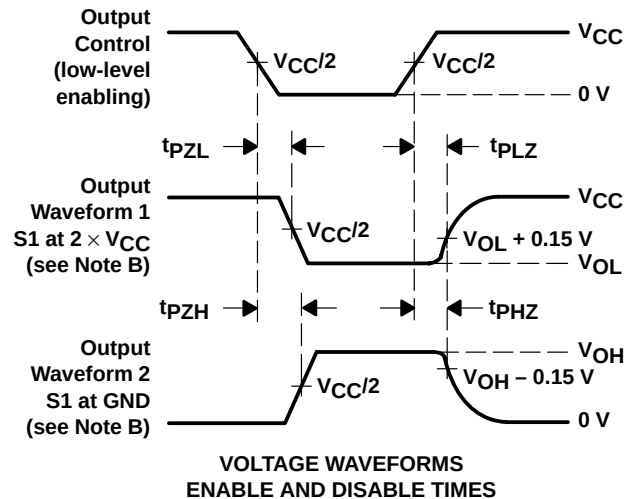
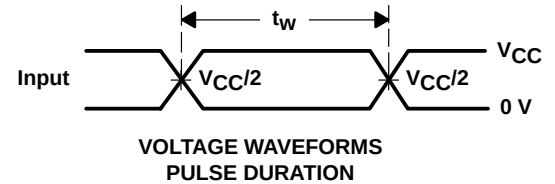
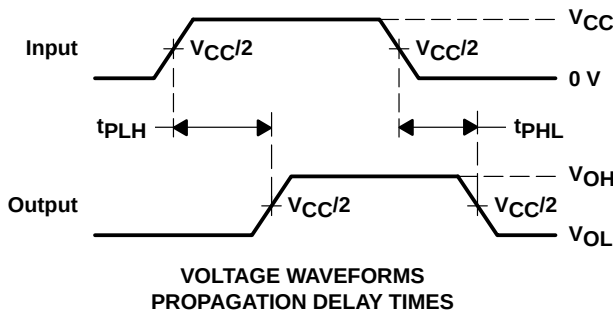
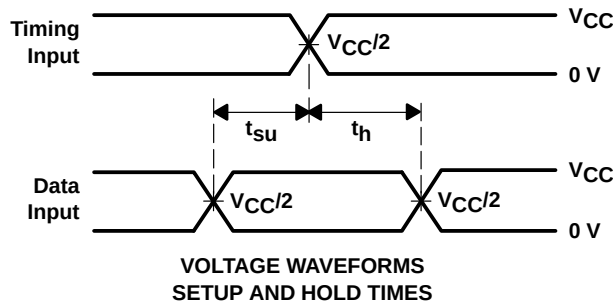
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PHZ}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH16821

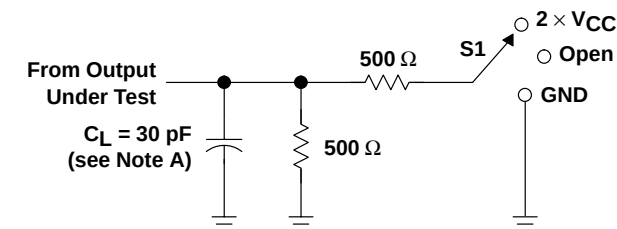
3.3-V 20-BIT BUS-INTERFACE FLIP-FLOP

WITH 3-STATE OUTPUTS

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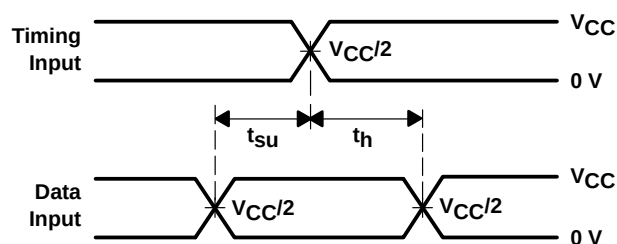
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

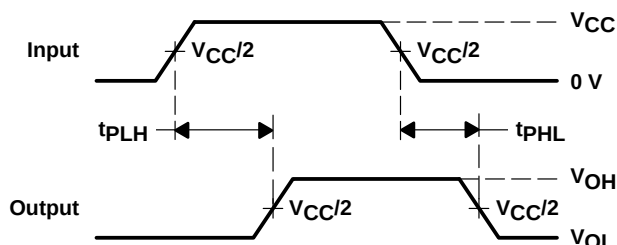


LOAD CIRCUIT

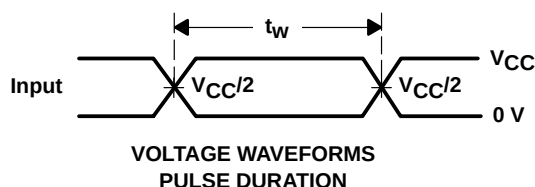
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



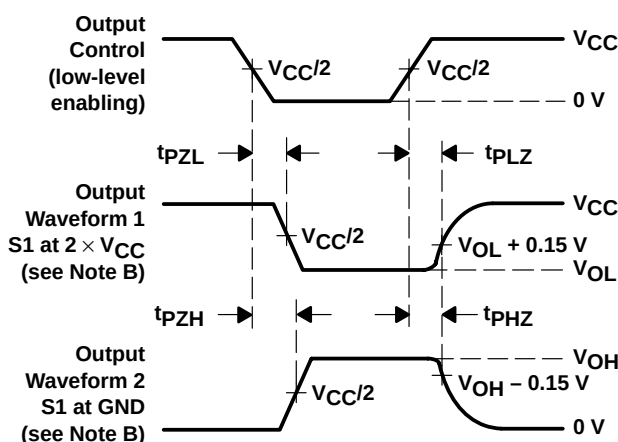
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



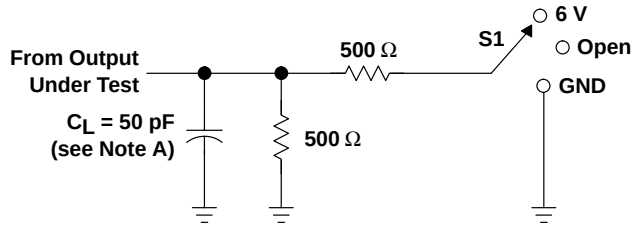
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

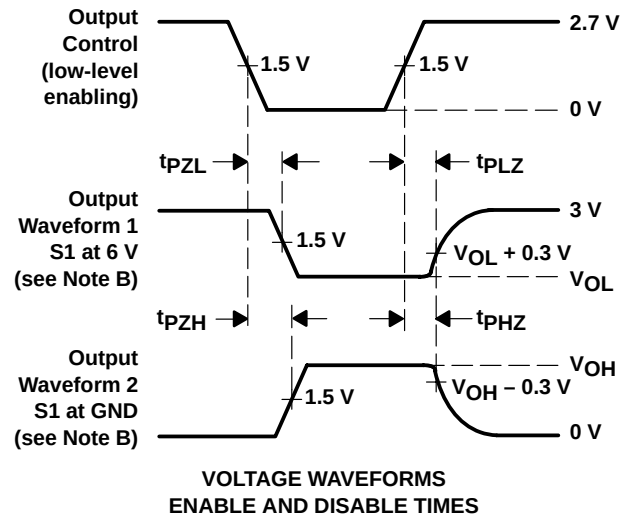
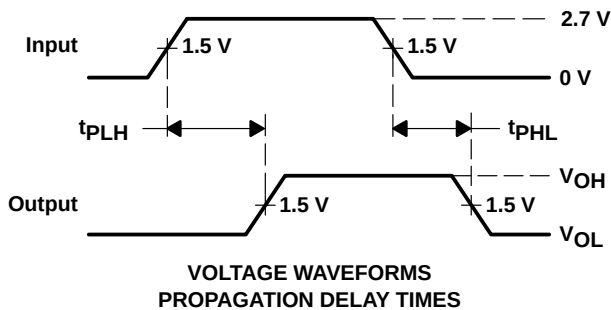
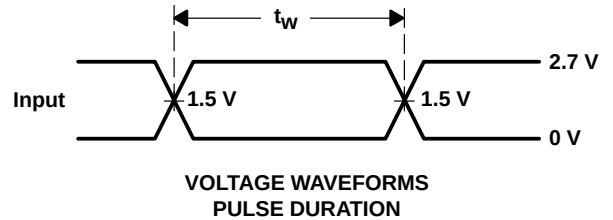
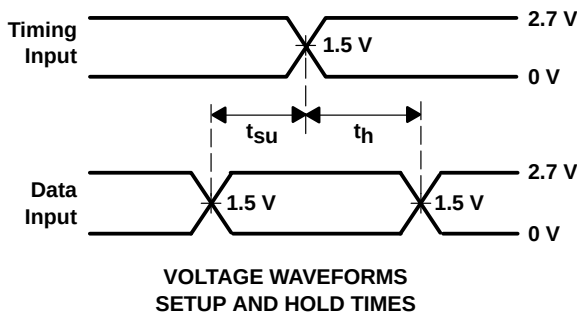
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16823

18-BIT BUS-INTERFACE FLIP-FLOP WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 18-bit bus-interface flip-flop is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16823 features 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. This device is particularly suitable for implementing wider buffer registers, I/O ports, bidirectional bus drivers with parity, and working registers.

The SN74ALVCH16823 can be used as two 9-bit flip-flops or one 18-bit flip-flop. With the clock-enable ($\overline{CLKEN}$) input low, the D-type flip-flops enter data on the low-to-high transitions of the clock. Taking $\overline{CLKEN}$ high disables the clock buffer, thus latching the outputs. Taking the clear ($\overline{CLR}$) input low causes the Q outputs to go low independently of the clock.

A buffered output-enable ($\overline{OE}$) input can be used to place the nine outputs in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without need for interface or pullup components.

The output-enable ($\overline{OE}$) input does not affect the internal operation of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16823 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE (TOP VIEW)

1 $\overline{CLR}$	1	56	1CLK
1 $\overline{OE}$	2	55	1 $\overline{CLKEN}$
1Q1	3	54	1D1
GND	4	53	GND
1Q2	5	52	1D2
1Q3	6	51	1D3
V_{CC}	7	50	V_{CC}
1Q4	8	49	1D4
1Q5	9	48	1D5
1Q6	10	47	1D6
GND	11	46	GND
1Q7	12	45	1D7
1Q8	13	44	1D8
1Q9	14	43	1D9
2Q1	15	42	2D1
2Q2	16	41	2D2
2Q3	17	40	2D3
GND	18	39	GND
2Q4	19	38	2D4
2Q5	20	37	2D5
2Q6	21	36	2D6
V_{CC}	22	35	V_{CC}
2Q7	23	34	2D7
2Q8	24	33	2D8
GND	25	32	GND
2Q9	26	31	2D9
2 $\overline{OE}$	27	30	2 $\overline{CLKEN}$
2 $\overline{CLR}$	28	29	2CLK

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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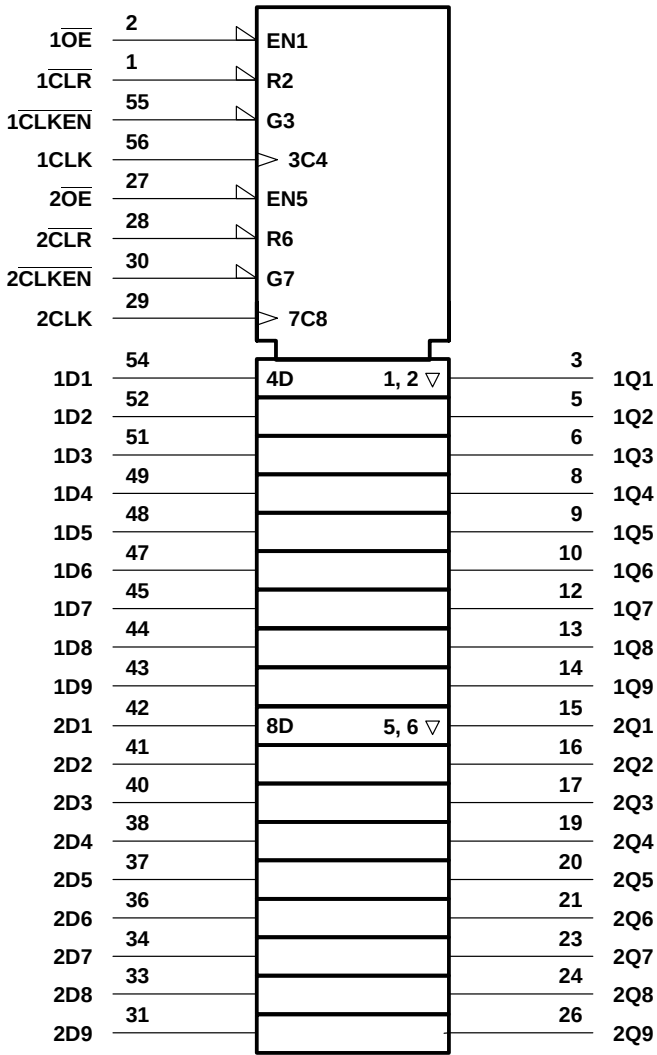
SN74ALVCH16823
18-BIT BUS-INTERFACE FLIP-FLOP
WITH 3-STATE OUTPUTS

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FUNCTION TABLE
(each 9-bit flip-flop)

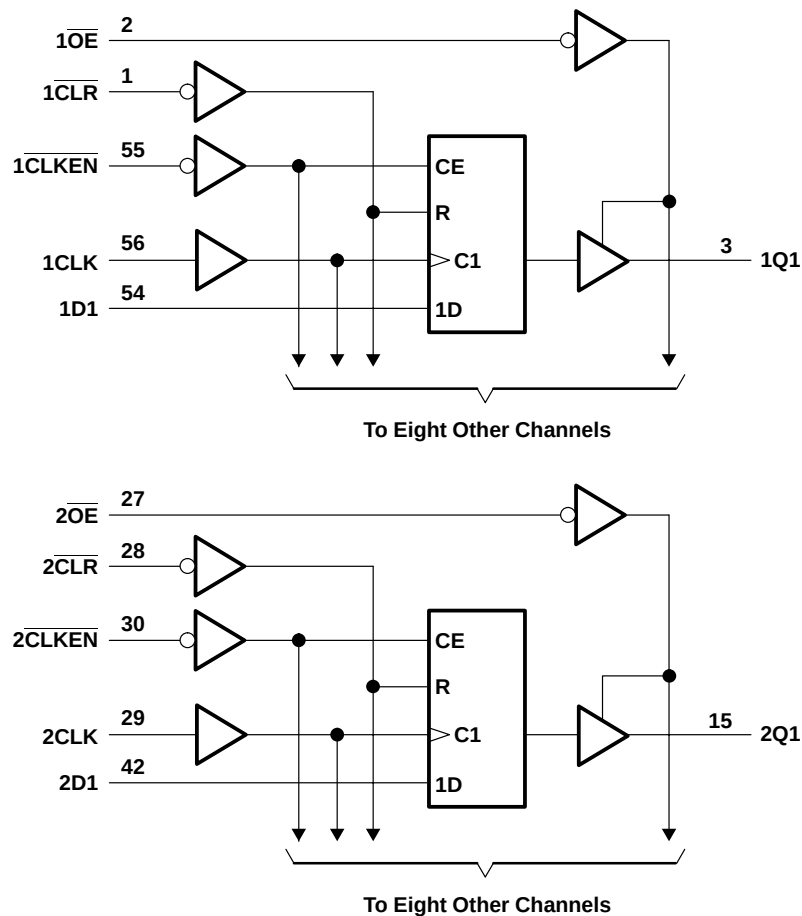
INPUTS					OUTPUT Q
OE	CLR	CLKEN	CLK	D	
L	L	X	X	X	L
L	H	L	↑	H	H
L	H	L	↑	L	L
L	H	L	L	X	Q ₀
L	H	H	X	X	Q ₀
H	X	X	X	X	Z

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{Stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

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18-BIT BUS-INTERFACE FLIP-FLOP WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–4	mA
		$V_{CC} = 2.3 \text{ V}$	–12	
		$V_{CC} = 2.7 \text{ V}$	–12	
		$V_{CC} = 3 \text{ V}$	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	4	mA
		$V_{CC} = 2.3 \text{ V}$	12	
		$V_{CC} = 2.7 \text{ V}$	12	
		$V_{CC} = 3 \text{ V}$	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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18-BIT BUS-INTERFACE FLIP-FLOP
WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
		I _{OL} = 12 mA	2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	4.5			pF
	Data inputs			6.5			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

SN74ALVCH16823

18-BIT BUS-INTERFACE FLIP-FLOP WITH 3-STATE OUTPUTS

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			V _{CC} = 1.8 V		V _{CC} = 2.5 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency		†		150		150		150		MHz
t _w	Pulse duration	CL $\overline{R}$ low	†		3.3		3.3		3.3		ns
		CLK high or low	†		3.3		3.3		3.3		
t _{su}	Setup time	CL $\overline{R}$ inactive	†		0.7		0.7		0.8		ns
		Data low before CLK↑	†		1.6		1.6		1.3		
		Data high before CLK↑	†		1.1		1.1		1		
		CL $\overline{KEN}$ low before CLK↑	†		1.9		1.9		1.5		
t _h	Hold time	Data low after CLK↑	†		0.5		0.5		0.5		ns
		Data high after CLK↑	†		0.1		0.1		0.8		
		CL $\overline{KEN}$ low after CLK↑	†		0.3		0.3		0.4		

† This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	CLK	Q	†		1	5.8	5.2		1	4.5	ns
	CL $\overline{R}$		†		1	5.4	5.2		1.2	4.6	
t _{en}	OE	Q	†		1	6	5.7		1	4.8	ns
t _{dis}	OE	Q	†		1.1	5.4	4.7		1.3	4.5	ns

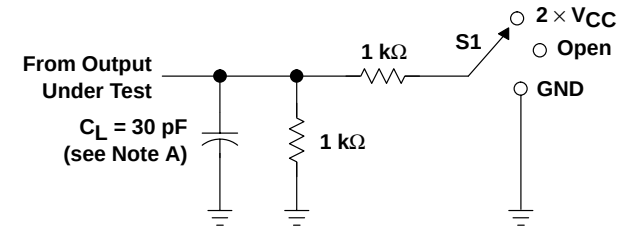
† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

PARAMETER		TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
			TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	C _L = 50 pF, f = 10 MHz	†	27	30	pF
	Outputs enabled		†	16	18	

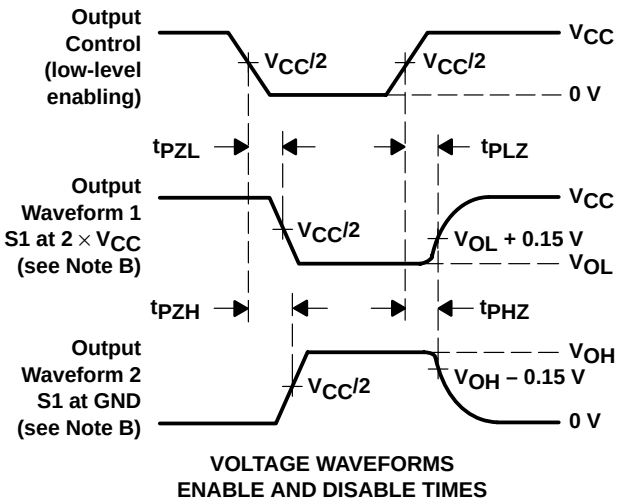
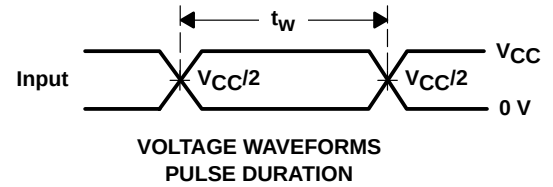
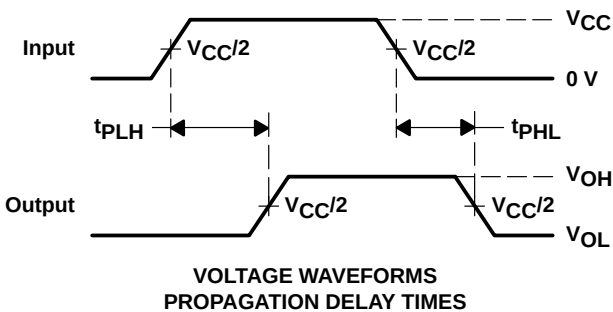
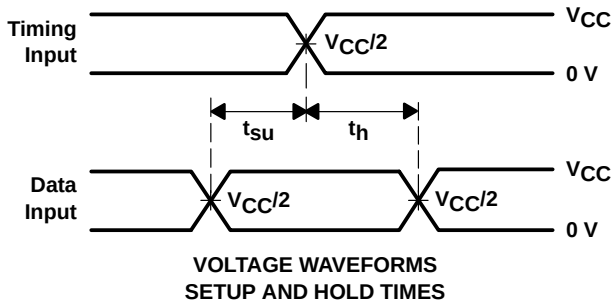
† This information was not available at the time of publication.

PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH16823

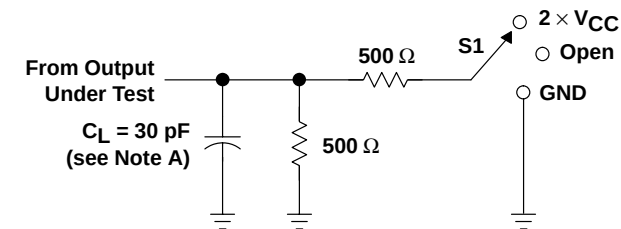
18-BIT BUS-INTERFACE FLIP-FLOP

WITH 3-STATE OUTPUTS

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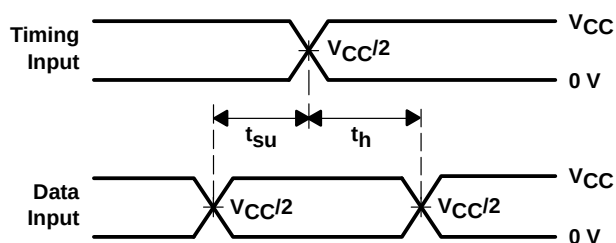
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

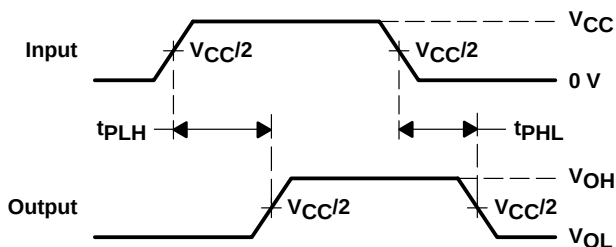


LOAD CIRCUIT

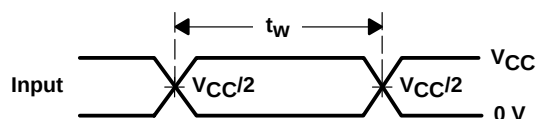
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



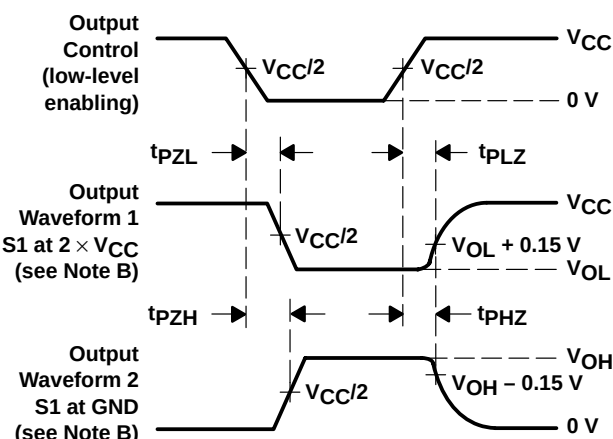
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



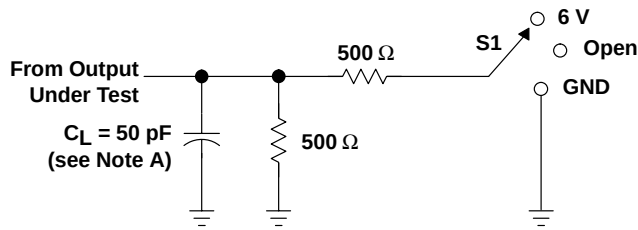
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

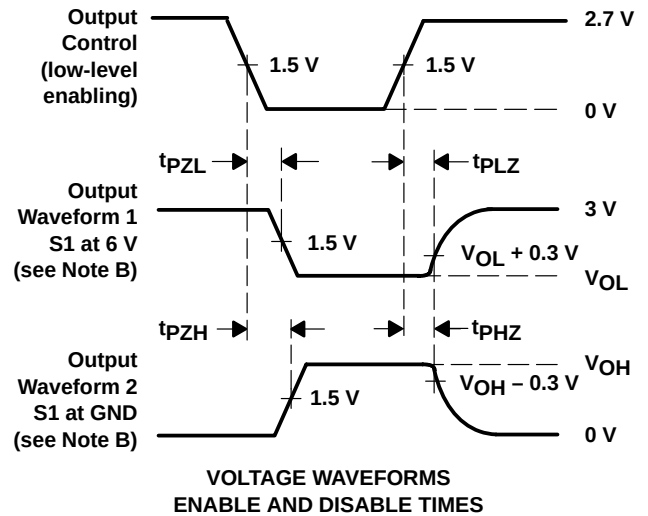
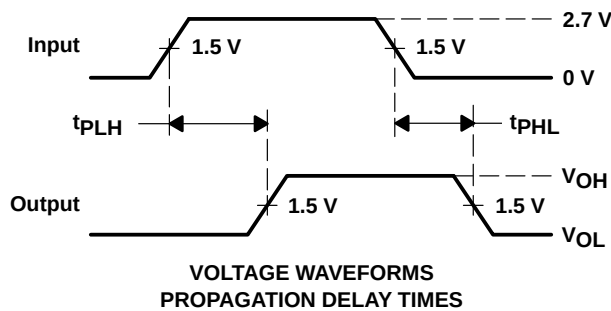
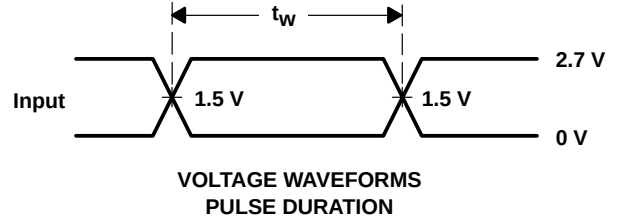
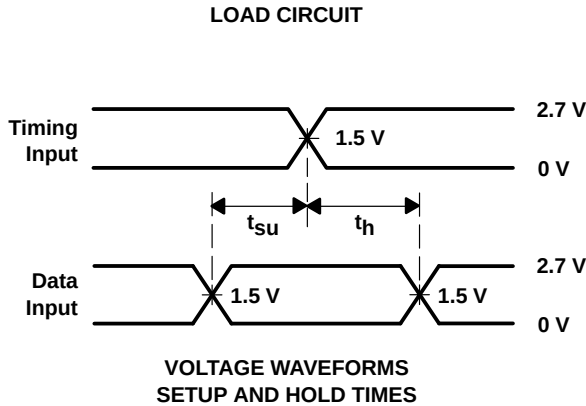
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16825

18-BIT BUFFER/DRIVER WITH 3-STATE OUTPUTS

SCES039C – JULY 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 18-bit buffer and line driver is designed for 1.65-V to 3.6-V V_{CC} operation.

This SN74ALVCH16825 improves the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters.

The device can be used as two 9-bit buffers or one 18-bit buffer. It provides true data.

The 3-state control gate is a 2-input AND gate with active-low inputs so that if either output-enable ($\overline{OE1}$ or $\overline{OE2}$) input is high, all nine affected outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating inputs at a valid logic level.

The SN74ALVCH16825 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE (TOP VIEW)

$\overline{1OE1}$	1	56	$\overline{1OE2}$
1Y1	2	55	1A1
1Y2	3	54	1A2
GND	4	53	GND
1Y3	5	52	1A3
1Y4	6	51	1A4
V_{CC}	7	50	V_{CC}
1Y5	8	49	1A5
1Y6	9	48	1A6
1Y7	10	47	1A7
GND	11	46	GND
1Y8	12	45	1A8
1Y9	13	44	1A9
GND	14	43	GND
GND	15	42	GND
2Y1	16	41	2A1
2Y2	17	40	2A2
GND	18	39	GND
2Y3	19	38	2A3
2Y4	20	37	2A4
2Y5	21	36	2A5
V_{CC}	22	35	V_{CC}
2Y6	23	34	2A6
2Y7	24	33	2A7
GND	25	32	GND
2Y8	26	31	2A8
2Y9	27	30	2A9
$\overline{2OE1}$	28	29	$\overline{2OE2}$

FUNCTION TABLE
(each 9-bit section)

INPUTS			OUTPUT Y
$\overline{OE1}$	$\overline{OE2}$	A	
L	L	L	L
L	L	H	H
H	X	X	Z
X	H	X	Z

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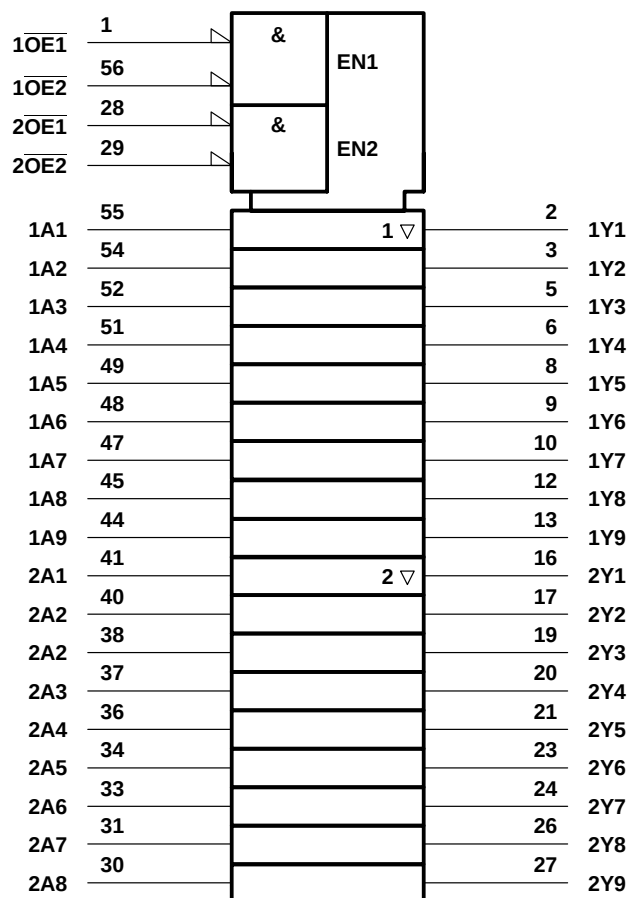
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SN74ALVCH16825

18-BIT BUFFER/DRIVER WITH 3-STATE OUTPUTS

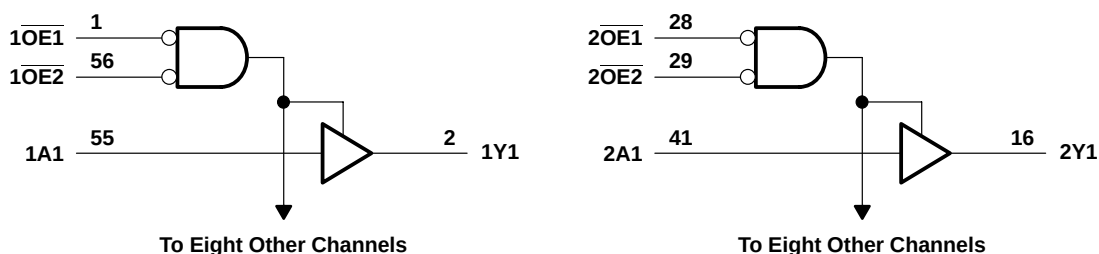
SCES039C – JULY 1995 – REVISED FEBRUARY 1999

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate			10	ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

SN74ALVCH16825
18-BIT BUFFER/DRIVER
WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	3.3 V	3.5			pF
	Data inputs		6			
C _O	Outputs	3.3 V	7.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	Y	§	1	4.1	3.9		1	3.4	ns
t _{en}	$\overline{\text{OE}}$	Y	§	1	6	5.7		1	4.7	ns
t _{dis}	$\overline{\text{OE}}$	Y	§	1.2	5.6	4.9		1.3	4.5	ns

§ This information was not available at the time of publication.



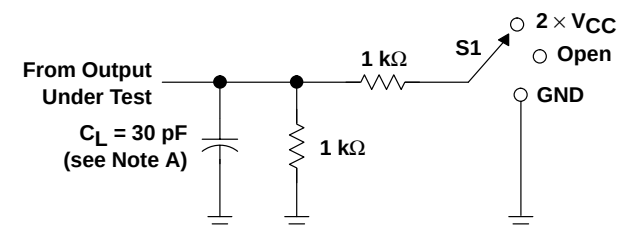
operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd} Power dissipation capacitance	Outputs enabled	$C_L = 50\text{ pF}, f = 10\text{ MHz}$	†	16	18	pF
	Outputs disabled		†	4	6	

† This information was not available at the time of publication.

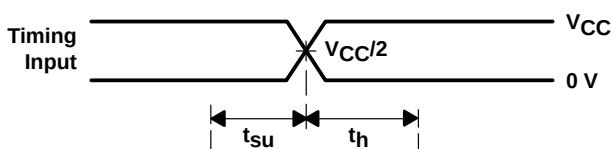
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8\text{ V}$

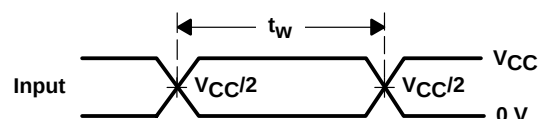


LOAD CIRCUIT

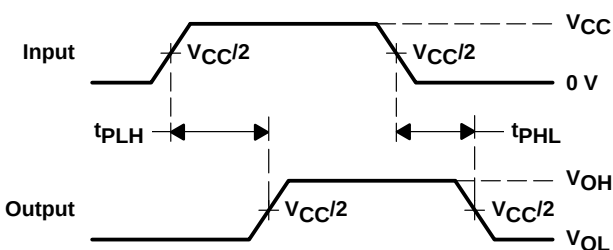
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



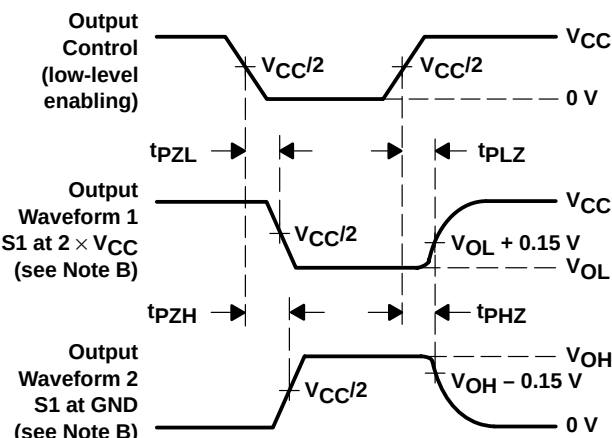
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH16825

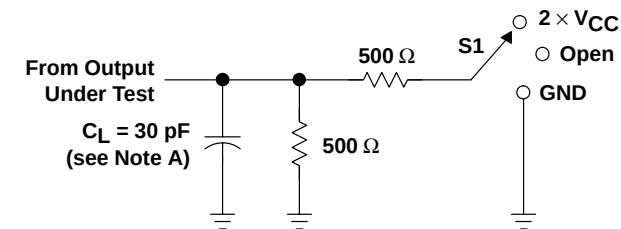
18-BIT BUFFER/DRIVER

WITH 3-STATE OUTPUTS

SCES039C – JULY 1995 – REVISED FEBRUARY 1999

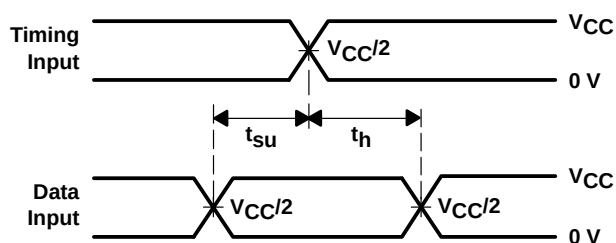
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

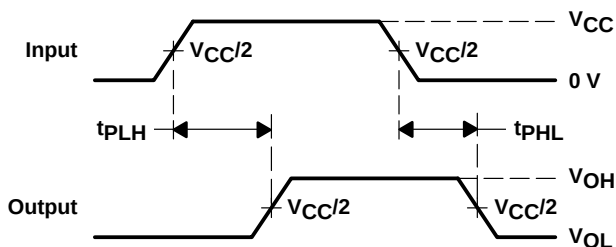


LOAD CIRCUIT

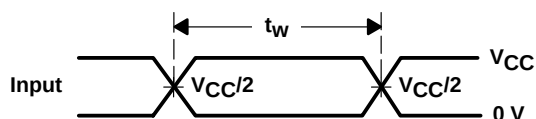
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



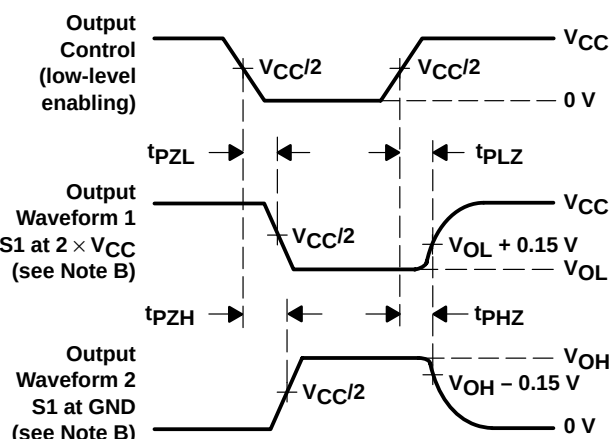
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



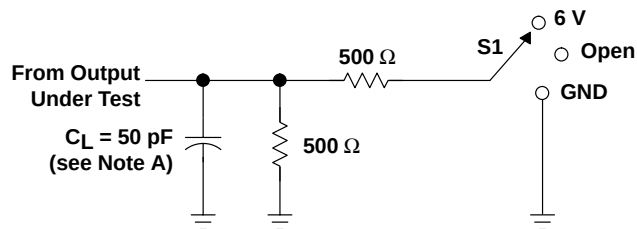
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

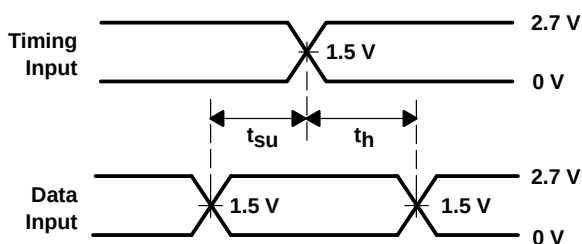
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

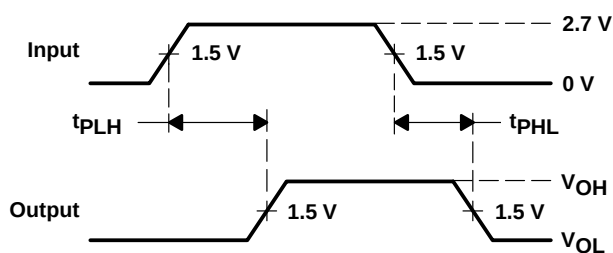


LOAD CIRCUIT

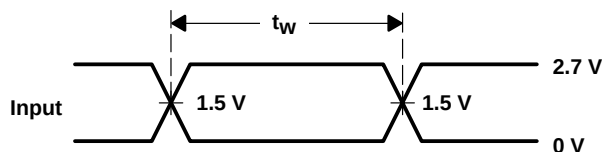
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



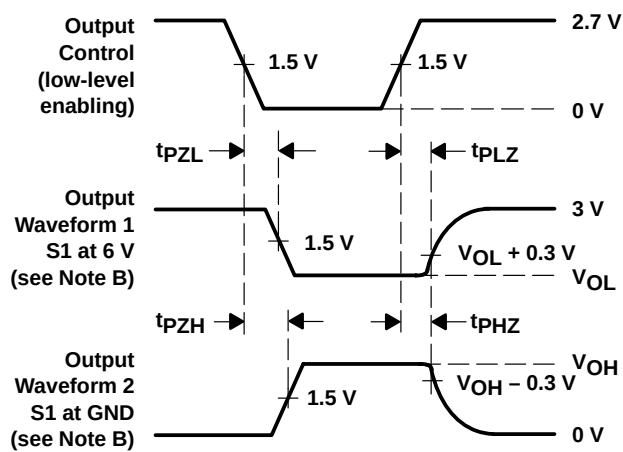
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16827 20-BIT BUFFER/DRIVER WITH 3-STATE OUTPUTS

SCES041C – JULY 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 20-bit noninverting buffer/driver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16827 is composed of two 10-bit sections with separate output-enable signals. For either 10-bit buffer section, the two output-enable ($\overline{1OE1}$ and $\overline{1OE2}$ or $\overline{2OE1}$ and $\overline{2OE2}$) inputs must both be low for the corresponding Y outputs to be active. If either output-enable input is high, the outputs of that 10-bit buffer section are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16827 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE (TOP VIEW)

$\overline{1OE1}$	1	56	$\overline{1OE2}$
1Y1	2	55	1A1
1Y2	3	54	1A2
GND	4	53	GND
1Y3	5	52	1A3
1Y4	6	51	1A4
V_{CC}	7	50	V_{CC}
1Y5	8	49	1A5
1Y6	9	48	1A6
1Y7	10	47	1A7
GND	11	46	GND
1Y8	12	45	1A8
1Y9	13	44	1A9
1Y10	14	43	1A10
2Y1	15	42	2A1
2Y2	16	41	2A2
2Y3	17	40	2A3
GND	18	39	GND
2Y4	19	38	2A4
2Y5	20	37	2A5
2Y6	21	36	2A6
V_{CC}	22	35	V_{CC}
2Y7	23	34	2A7
2Y8	24	33	2A8
GND	25	32	GND
2Y9	26	31	2A9
2Y10	27	30	2A10
$\overline{2OE1}$	28	29	$\overline{2OE2}$

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



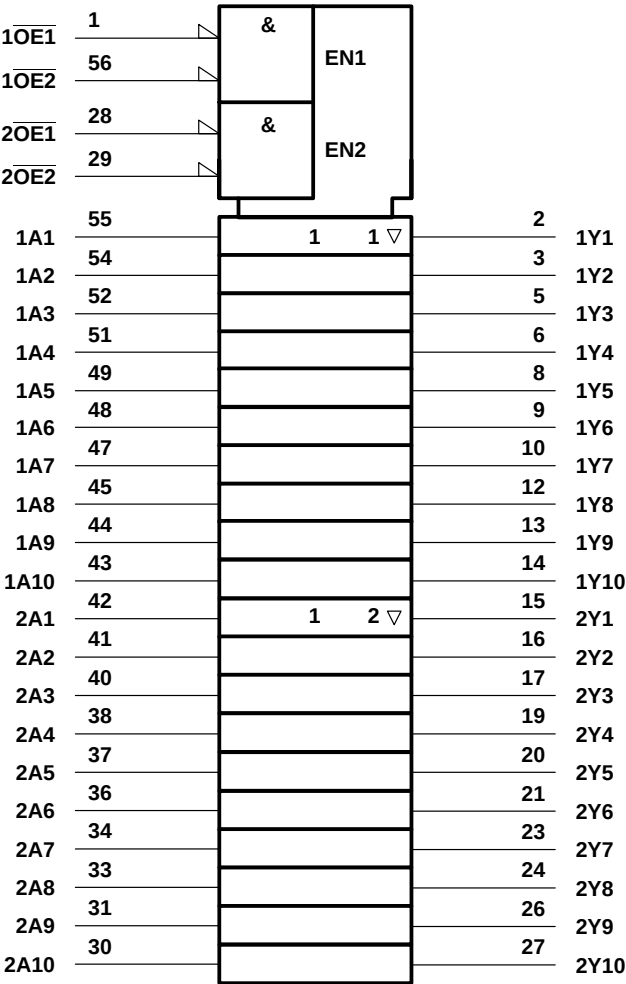
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FUNCTION TABLE
(each 10-bit section)

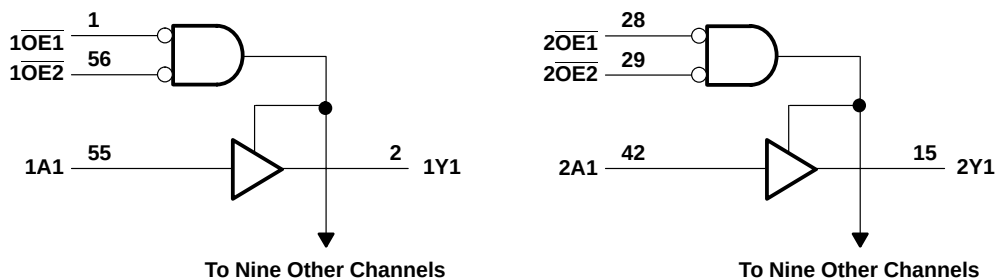
INPUTS			OUTPUT Y
OE1	OE2	A	
L	L	L	L
L	L	H	H
H	X	X	Z
X	H	X	Z

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

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20-BIT BUFFER/DRIVER
WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–4	mA
		$V_{CC} = 2.3 \text{ V}$	–12	
		$V_{CC} = 2.7 \text{ V}$	–12	
		$V_{CC} = 3 \text{ V}$	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	4	mA
		$V_{CC} = 2.3 \text{ V}$	12	
		$V_{CC} = 2.7 \text{ V}$	12	
		$V_{CC} = 3 \text{ V}$	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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20-BIT BUFFER/DRIVER
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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V		3.5	pF
	Data inputs				6	
C _O	Outputs	V _O = V _{CC} or GND	3.3 V		7.5	pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	Y	§	1	4.1	3.9		1	3.4	ns
t _{en}	OE	Y	§	1	6	5.7		1	4.7	ns
t _{dis}	OE	Y	§	1.2	5.6	4.9		1.3	4.5	ns

§ This information was not available at the time of publication.



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20-BIT BUFFER/DRIVER
WITH 3-STATE OUTPUTS

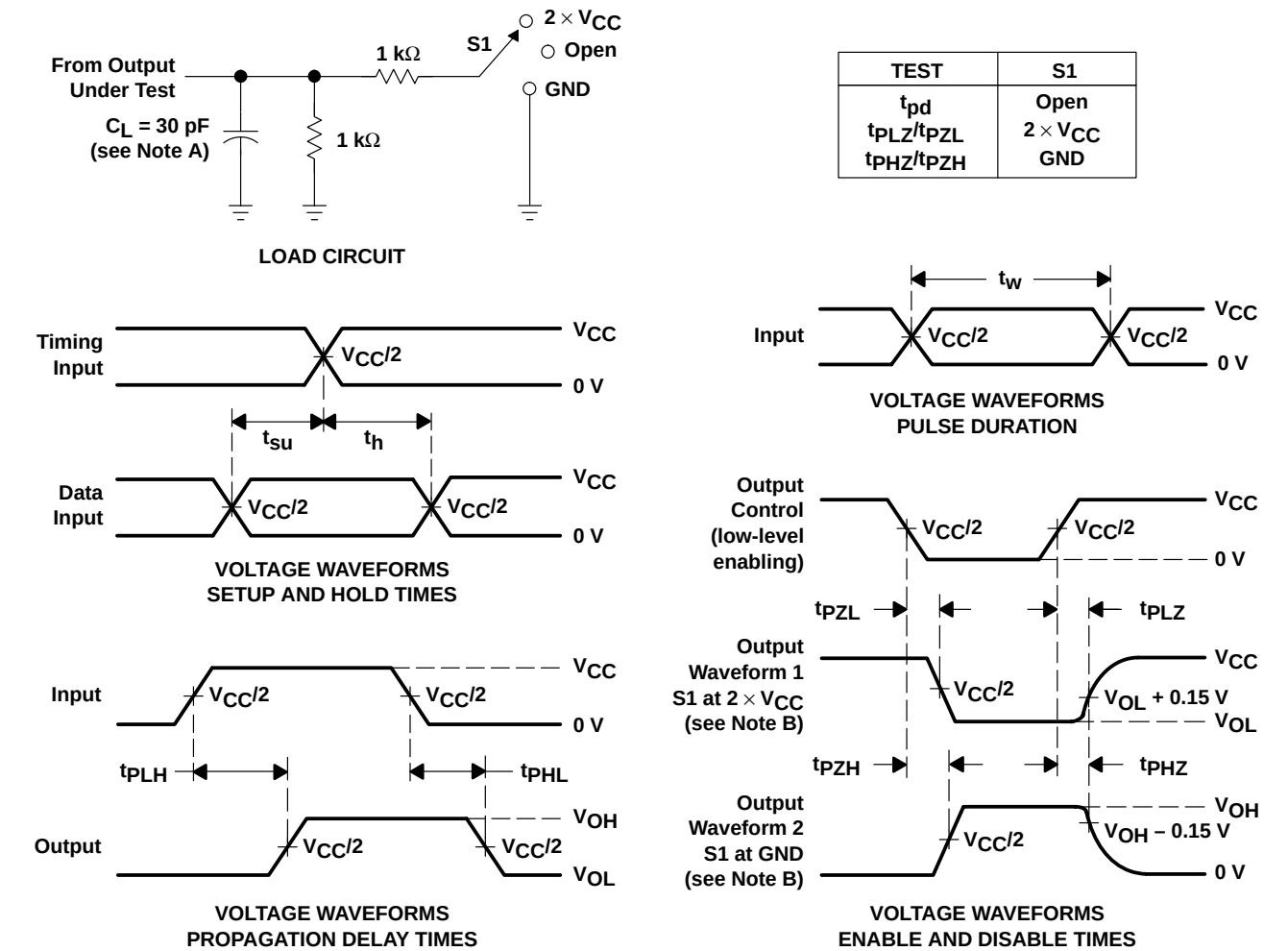
SCES041C – JULY 1995 – REVISED FEBRUARY 1999

operating characteristics, $T_A = 25^{\circ}\text{C}$

PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd} Power dissipation capacitance	Outputs enabled	$C_L = 50\text{ pF}, f = 10\text{ MHz}$	†	16	18	pF
	Outputs disabled		†	4	6	

† This information was not available at the time of publication.

PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8\text{ V}$

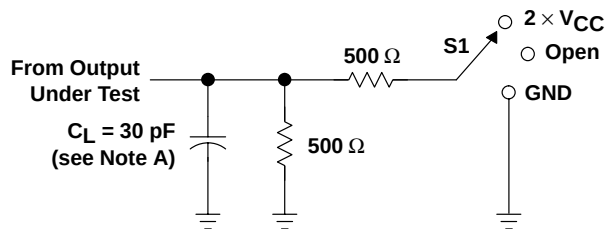


- NOTES: A. C_L includes probe and jig capacitance.
 B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r ≤ 2 ns, t_f ≤ 2 ns.
 D. The outputs are measured one at a time with one transition per measurement.
 E. t_{pLZ} and t_{pHZ} are the same as t_{dis}.
 F. t_{pZL} and t_{pZH} are the same as t_{en}.
 G. t_{PLH} and t_{PHL} are the same as t_{pd}.

Figure 1. Load Circuit and Voltage Waveforms

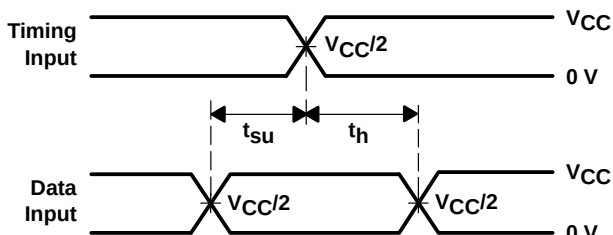
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

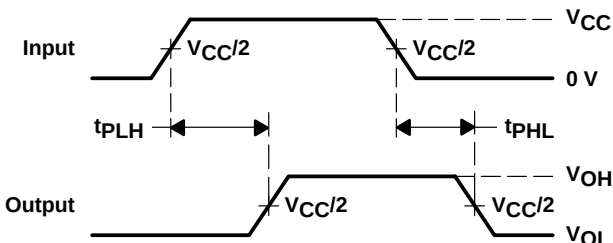


LOAD CIRCUIT

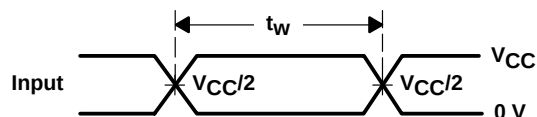
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



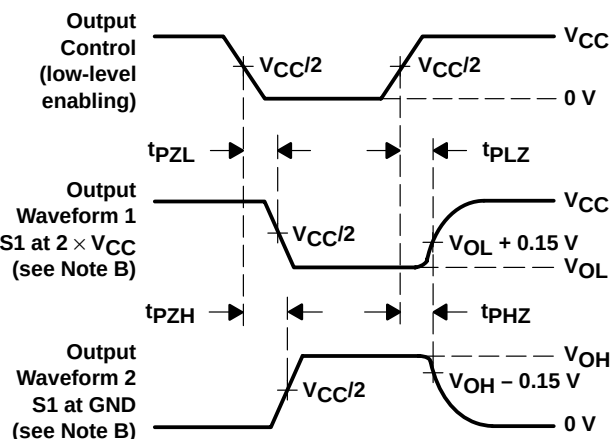
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

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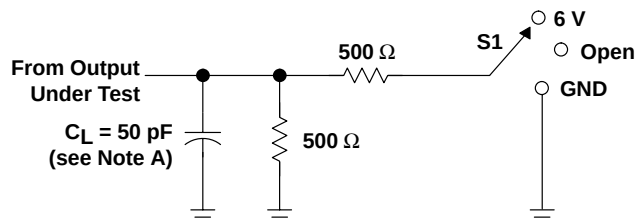
20-BIT BUFFER/DRIVER

WITH 3-STATE OUTPUTS

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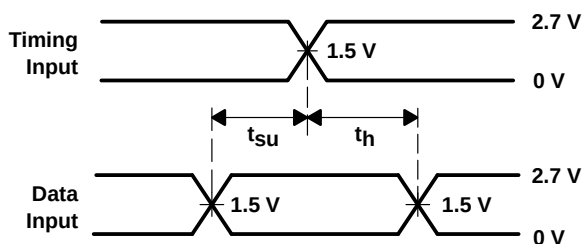
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$

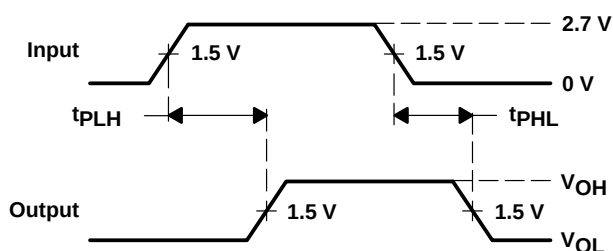


LOAD CIRCUIT

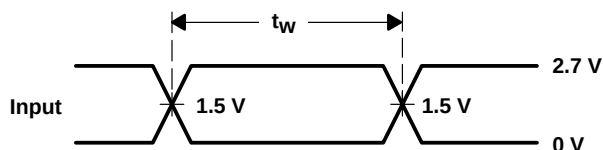
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



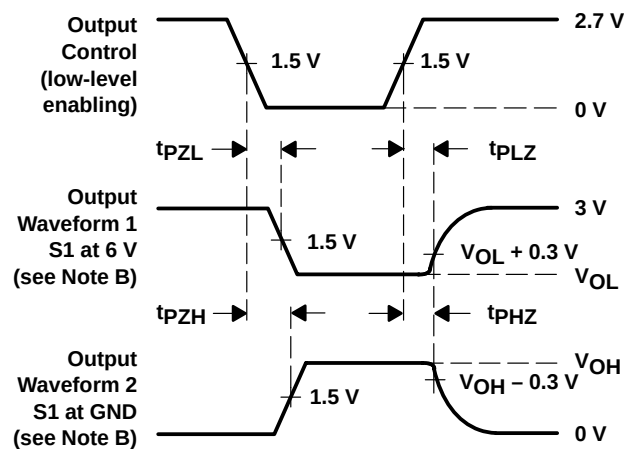
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES: A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
- D. The outputs are measured one at a time with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16828 20-BIT BUFFER/DRIVER WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 20-bit inverting buffer/driver is designed for 1.65-V to 3.6-V V_{CC} operation.

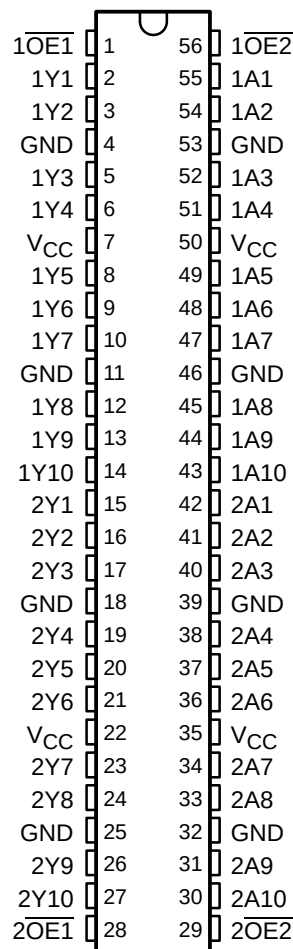
The SN74ALVCH16828 is composed of two 10-bit sections with separate output-enable signals. For either 10-bit buffer section, the two output-enable ($\overline{1OE1}$ and $\overline{1OE2}$ or $\overline{2OE1}$ and $\overline{2OE2}$) inputs must both be low for the corresponding Y outputs to be active. If either output-enable input is high, the outputs of that 10-bit buffer section are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating inputs at a valid logic level.

The SN74ALVCH16828 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)



FUNCTION TABLE
(each 10-bit section)

INPUTS			OUTPUT Y
$\overline{OE1}$	$\overline{OE2}$	A	
L	L	L	H
L	L	H	L
H	X	X	Z
X	H	X	Z

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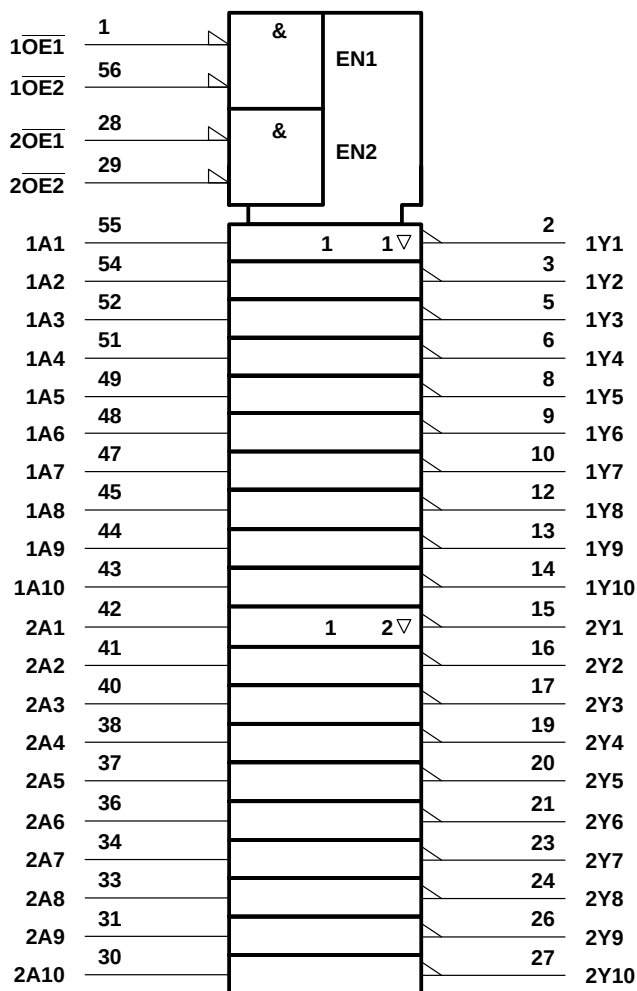
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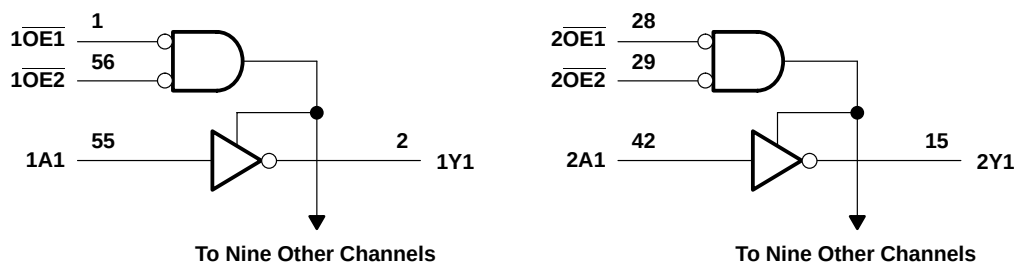
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logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate			10	ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	3.3 V				pF
	Data inputs					
C _O	Outputs	3.3 V				pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	Y								ns
t _{en}	$\overline{\text{OE}}$	Y								ns
t _{dis}	$\overline{\text{OE}}$	Y								ns

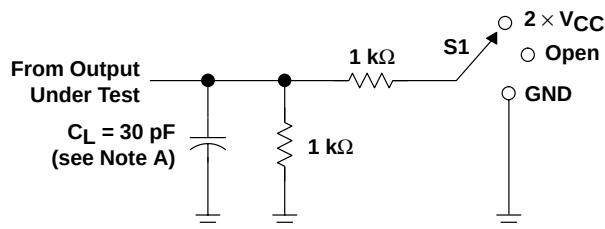


operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd} Power dissipation capacitance	Outputs enabled	$C_L = 0$, $f = 10\text{ MHz}$				pF
	Outputs disabled					

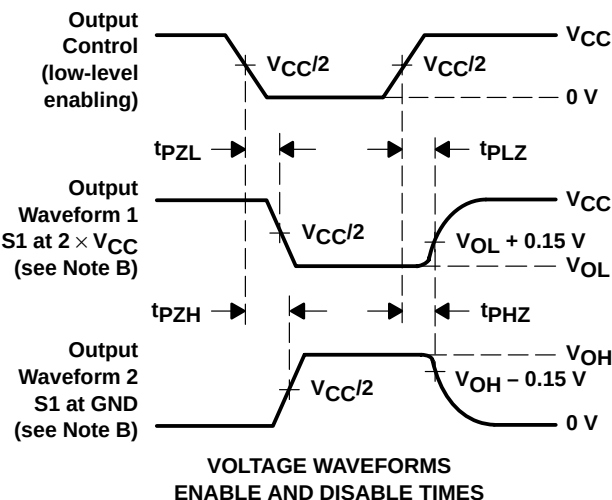
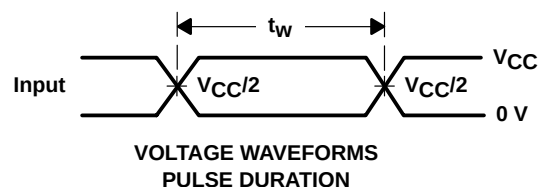
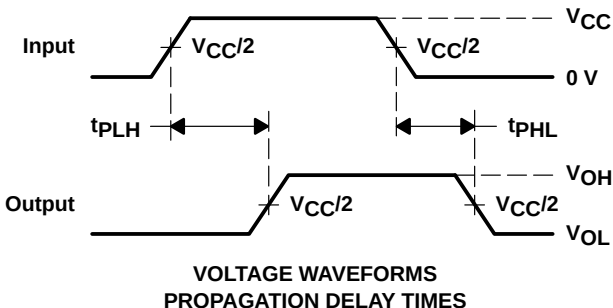
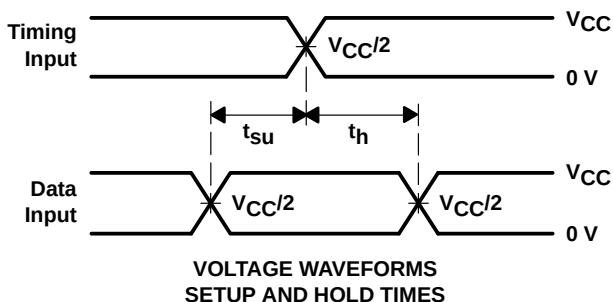
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	$2 \times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH16828

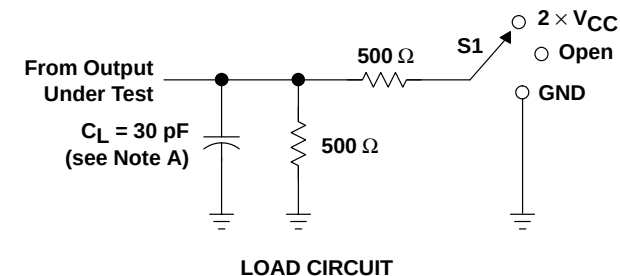
20-BIT BUFFER/DRIVER

WITH 3-STATE OUTPUTS

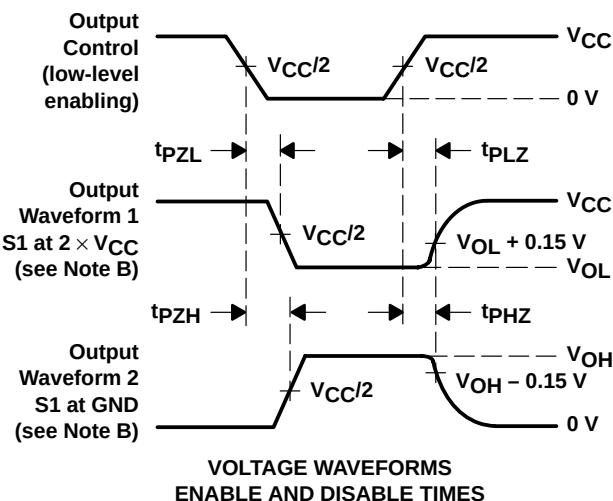
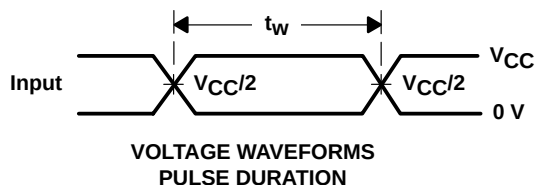
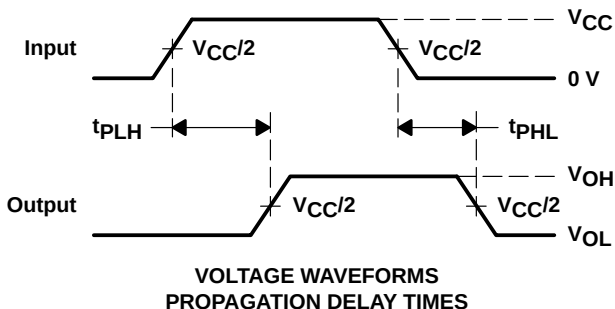
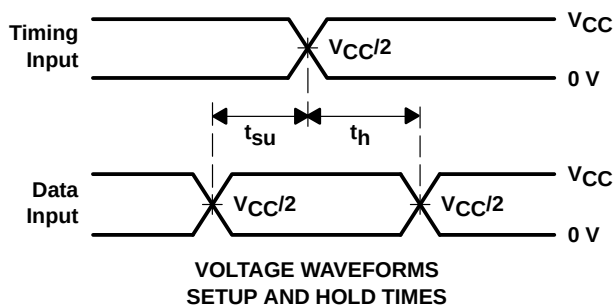
SCES042B – JULY 1995 – REVISED FEBRUARY 1999

PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$



TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND

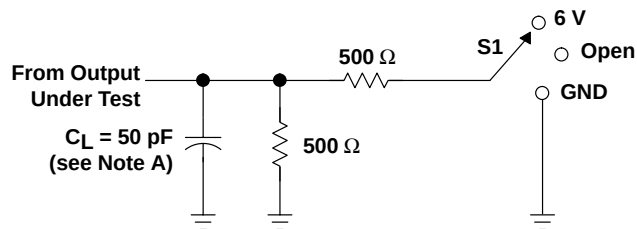


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

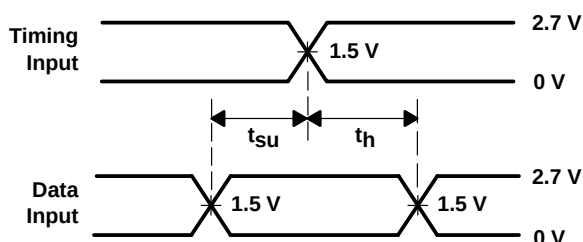
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

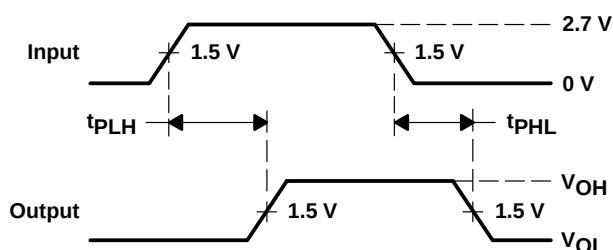


LOAD CIRCUIT

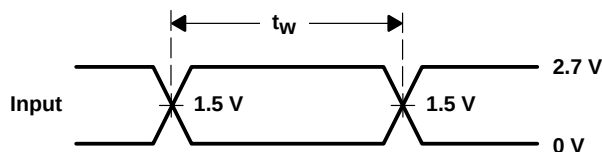
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



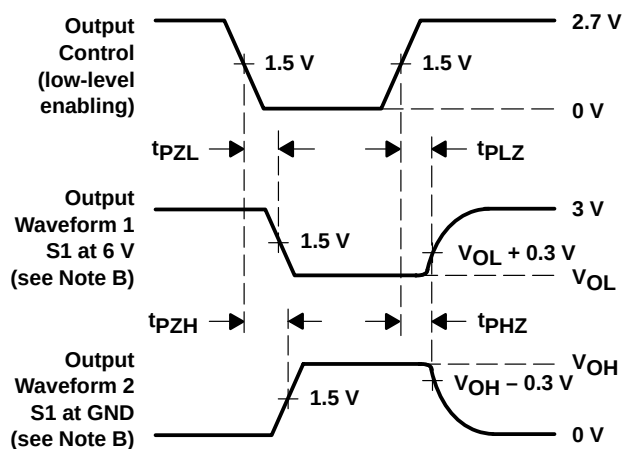
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16830 1-BIT TO 2-BIT ADDRESS DRIVER WITH 3-STATE OUTPUTS

SCES081B – AUGUST 1996 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Plastic 300-mil Thin Shrink Small-Outline Package

description

This 1-bit to 2-bit address driver is designed for 1.65-V to 3.6-V V_{CC} operation.

Active bus-hold circuitry is provided to hold unused or floating inputs at a valid logic level.

To ensure the high-impedance state during power up or power down, the output-enable ($\overline{OE}$) input should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74ALVCH16830 is characterized for operation from -40°C to 85°C .

FUNCTION TABLE

INPUTS			OUTPUTS	
$\overline{OE1}$	$\overline{OE2}$	A	1Yn	2Yn
L	H	H	H	Z
L	H	L	L	Z
H	L	H	Z	H
H	L	L	Z	L
L	L	H	H	H
L	L	L	L	L
H	H	X	Z	Z

DBB PACKAGE
(TOP VIEW)

2Y2	1	80	1Y3
1Y2	2	79	2Y3
GND	3	78	GND
2Y1	4	77	1Y4
1Y1	5	76	2Y4
V_{CC}	6	75	V_{CC}
A1	7	74	1Y5
A2	8	73	2Y5
GND	9	72	GND
A3	10	71	1Y6
A4	11	70	2Y6
GND	12	69	GND
A5	13	68	1Y7
A6	14	67	2Y7
V_{CC}	15	66	V_{CC}
A7	16	65	1Y8
A8	17	64	2Y8
GND	18	63	GND
A9	19	62	1Y9
$\overline{OE1}$	20	61	2Y9
$\overline{OE2}$	21	60	1Y10
A10	22	59	2Y10
GND	23	58	GND
A11	24	57	1Y11
A12	25	56	2Y11
V_{CC}	26	55	V_{CC}
A13	27	54	1Y12
A14	28	53	2Y12
GND	29	52	GND
A15	30	51	1Y13
A16	31	50	2Y13
GND	32	49	GND
A17	33	48	1Y14
A18	34	47	2Y14
V_{CC}	35	46	V_{CC}
2Y18	36	45	1Y15
1Y18	37	44	2Y15
GND	38	43	GND
2Y17	39	42	1Y16
1Y17	40	41	2Y16

PRODUCT PREVIEW

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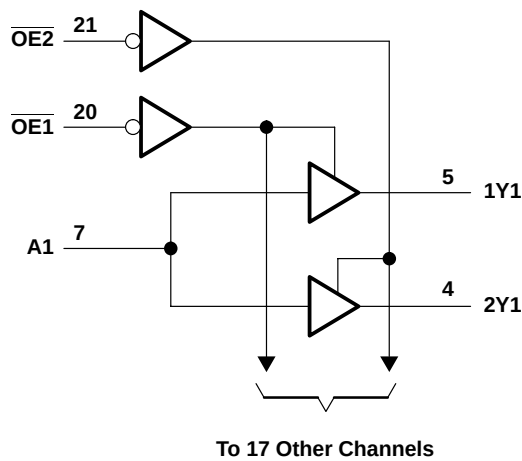


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SN74ALVCH16830
1-BIT TO 2-BIT ADDRESS DRIVER
WITH 3-STATE OUTPUTS
SCES081B – AUGUST 1996 – REVISED FEBRUARY 1999

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3)	106°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

SN74ALVCH16830
1-BIT TO 2-BIT ADDRESS DRIVER
WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate			10	ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

PRODUCT PREVIEW



SN74ALVCH16830
1-BIT TO 2-BIT ADDRESS DRIVER
WITH 3-STATE OUTPUTS

SCES081B – AUGUST 1996 – REVISED FEBRUARY 1999

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT	
V _{OH}		I _{OH} = –100 μA	1.65 V to 3.6 V	V _{CC} –0.2			V	
		I _{OH} = –4 mA	1.65 V	1.2				
		I _{OH} = –6 mA	2.3 V	2				
	I _{OH} = –12 mA		2.3 V	1.7				
			2.7 V	2.2				
			3 V	2.4				
		I _{OH} = –24 mA	3 V	2				
V _{OL}		I _{OL} = 100 μA	1.65 V to 3.6 V	0.2			V	
		I _{OL} = 4 mA	1.65 V	0.45				
		I _{OL} = 6 mA	2.3 V	0.4				
	I _{OL} = 12 mA		2.3 V	0.7				
			2.7 V	0.4				
		I _{OL} = 24 mA	3 V	0.55				
I _I		V _I = V _{CC} or GND	3.6 V	±5			μA	
I _I (hold)		V _I = 0.58 V	1.65 V	25			μA	
		V _I = 1.07 V	1.65 V	–25				
		V _I = 0.7 V	2.3 V	45				
		V _I = 1.7 V	2.3 V	–45				
		V _I = 0.8 V	3 V	75				
		V _I = 2 V	3 V	–75				
		V _I = 0 to 3.6 V [‡]	3.6 V	±500				
	I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			μA	
ΔI _{CC}			One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			μA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V				pF	
	Data inputs							
C _O	Outputs	V _O = V _{CC} or GND	3.3 V				pF	

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

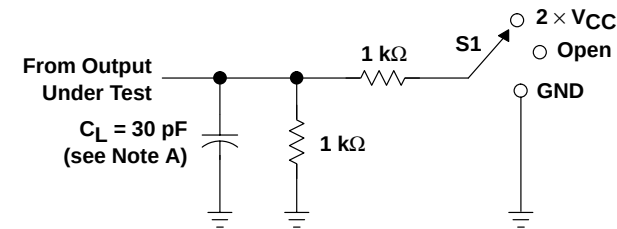
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	Y								ns
t _{en}	$\overline{\text{OE}}$	Y								ns
t _{dis}	$\overline{\text{OE}}$	Y								ns



operating characteristics, $T_A = 25^\circ\text{C}$

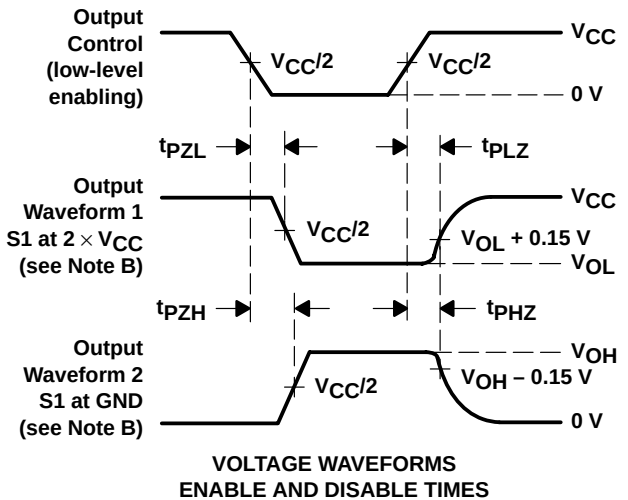
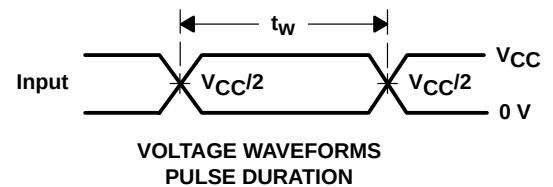
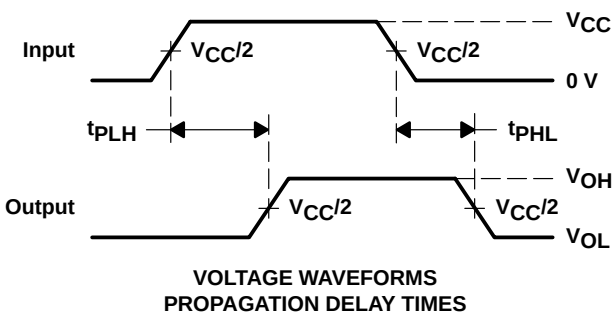
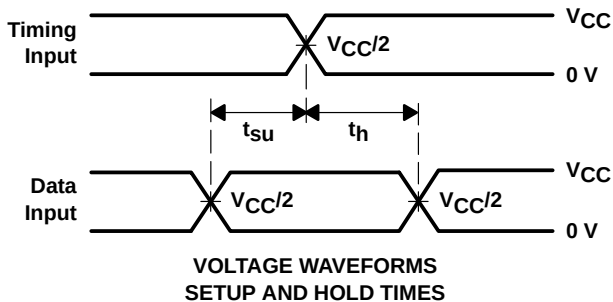
PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd} Power dissipation capacitance	Outputs enabled	$C_L = 0$, $f = 10\text{ MHz}$				pF
	Outputs disabled					

PARAMETER MEASUREMENT INFORMATION $V_{CC} = 1.8\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

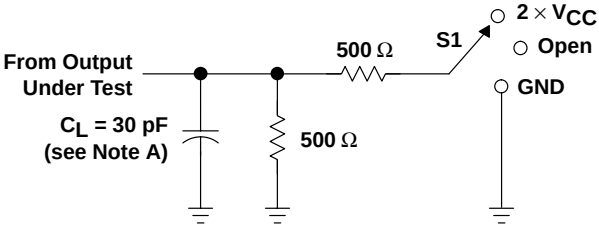
Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH16830
1-BIT TO 2-BIT ADDRESS DRIVER
WITH 3-STATE OUTPUTS

SCES081B – AUGUST 1996 – REVISED FEBRUARY 1999

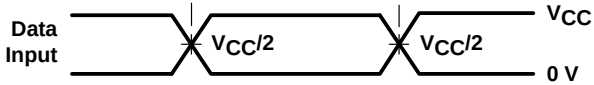
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$

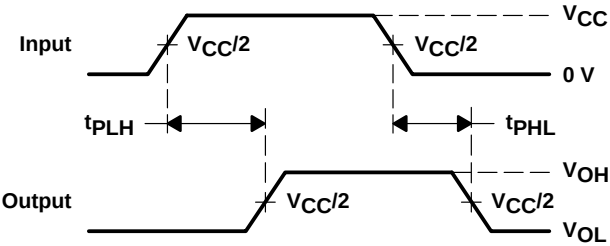


LOAD CIRCUIT

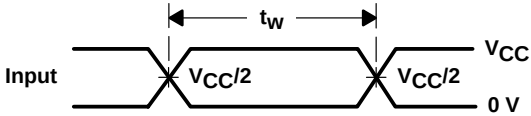
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



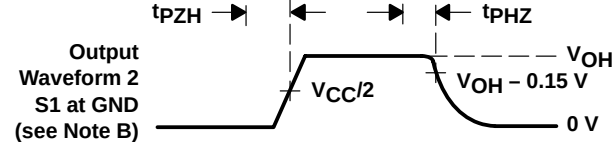
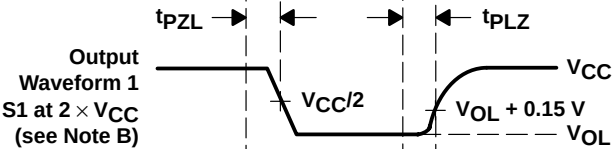
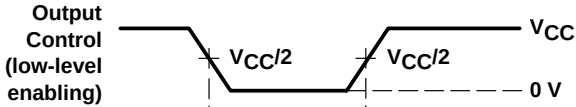
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



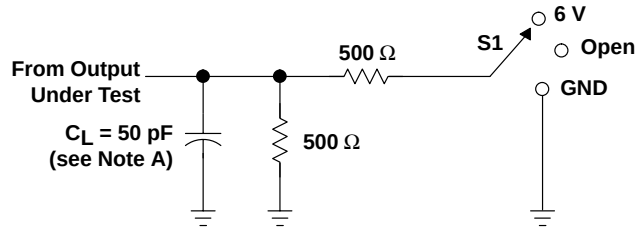
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

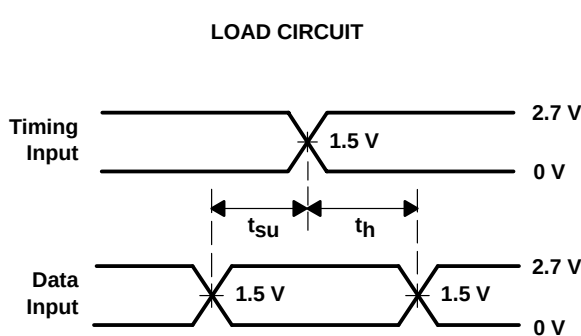
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

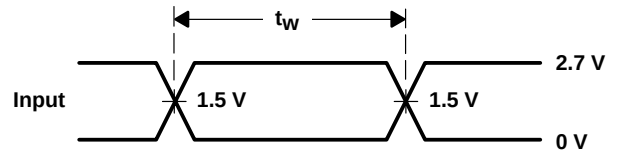


LOAD CIRCUIT

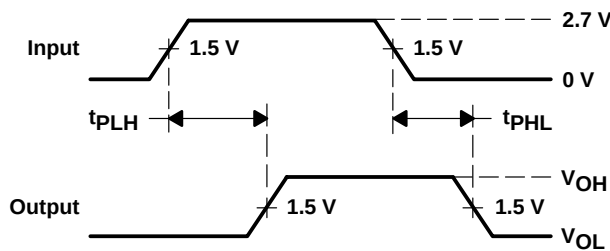
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



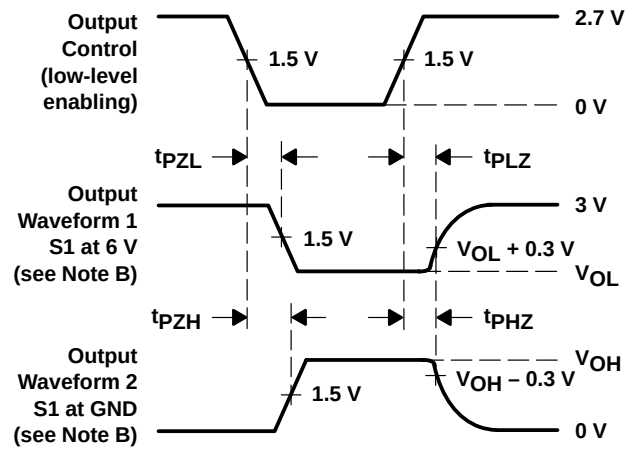
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16831 1-TO-4 ADDRESS REGISTER/DRIVER WITH 3-STATE OUTPUTS

SCES083D – AUGUST 1996 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Packaged in Thin Very Small-Outline Package

description

This 1-bit to 4-bit address register/driver is designed for 1.65-V to 3.6-V V_{CC} operation. The device is ideal for use in applications in which a single address bus is driving four separate memory locations. The SN74ALVCH16831 can be used as a buffer or a register, depending on the logic level of the select ($\overline{SEL}$) input.

When $\overline{SEL}$ is logic high, the device is in the buffer mode. The outputs follow the inputs and are controlled by the two output-enable ($\overline{OE}$) controls. Each $\overline{OE}$ controls two groups of nine outputs.

When $\overline{SEL}$ is logic low, the device is in the register mode. The register is an edge-triggered D-type flip-flop. On the positive transition of the clock (CLK) input, data set up at the A inputs is stored in the internal registers. $\overline{OE}$ controls operate the same as in buffer mode.

When $\overline{OE}$ is logic low, the outputs are in a normal logic state (high or low logic level). When $\overline{OE}$ is logic high, the outputs are in the high-impedance state.

$\overline{SEL}$ and $\overline{OE}$ do not affect the internal operation of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

DBB PACKAGE
(TOP VIEW)

4Y1	1	80	1Y2
3Y1	2	79	2Y2
GND	3	78	GND
2Y1	4	77	3Y2
1Y1	5	76	4Y2
V_{CC}	6	75	V_{CC}
NC	7	74	1Y3
A1	8	73	2Y3
GND	9	72	GND
NC	10	71	3Y3
A2	11	70	4Y3
GND	12	69	GND
NC	13	68	1Y4
A3	14	67	2Y4
V_{CC}	15	66	V_{CC}
NC	16	65	3Y4
A4	17	64	4Y4
GND	18	63	GND
CLK	19	62	1Y5
$\overline{OE1}$	20	61	2Y5
$\overline{OE2}$	21	60	3Y5
$\overline{SEL}$	22	59	4Y5
GND	23	58	GND
A5	24	57	1Y6
A6	25	56	2Y6
V_{CC}	26	55	V_{CC}
A7	27	54	3Y6
NC	28	53	4Y6
GND	29	52	GND
A8	30	51	1Y7
NC	31	50	2Y7
GND	32	49	GND
A9	33	48	3Y7
NC	34	47	4Y7
V_{CC}	35	46	V_{CC}
4Y9	36	45	1Y8
3Y9	37	44	2Y8
GND	38	43	GND
2Y9	39	42	3Y8
1Y9	40	41	4Y8

NC – No internal connection

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SN74ALVCH16831
1-TO-4 ADDRESS REGISTER/DRIVER
WITH 3-STATE OUTPUTS

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description (continued)

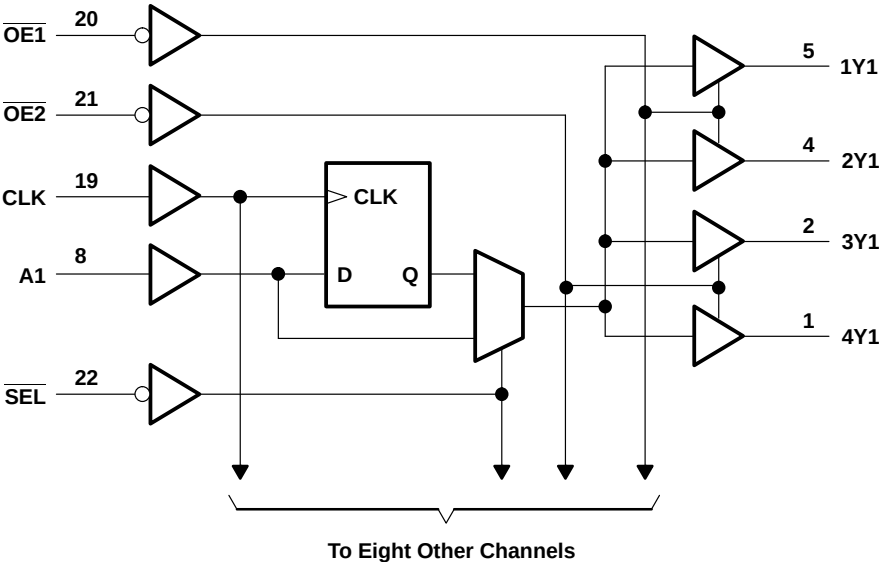
To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16831 is characterized for operation from -40°C to 85°C .

FUNCTION TABLE				
INPUTS				OUTPUT Y
$\overline{OE}$	$\overline{SEL}$	CLK	A	
H	X	X	X	Z
L	H	X	L	L
L	H	X	H	H
L	L	$\uparrow$	L	L
L	L	$\uparrow$	H	H

logic diagram (positive logic)



SN74ALVCH16831
1-TO-4 ADDRESS REGISTER/DRIVER
WITH 3-STATE OUTPUTS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3)	106°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	3.3 V	4.5			pF
	Data inputs		5			
C _O	Outputs	3.3 V	7.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency	§		150		150		150		MHz
t _w	Pulse duration, CLK high or low	§		3.3		3.3		3.3		ns
t _{su}	Setup time, A data before CLK↑	§		2		2		1.6		ns
t _h	Hold time, A data after CLK↑	§		0.7		0.5		1.1		ns

§ This information was not available at the time of publication.



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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	A	Y		†	1.2	4	4.1		1.6	3.6	ns
	CLK			†	1.1	4.5	4.4		1.5	3.9	
	SEL			†	1.3	5.2	5.2		1.7	4.4	
t _{en}	OE	Y		†	1.1	5.1	5		1.2	4.3	ns
t _{dis}	OE	Y		†	1.4	5.5	4.7		1.6	4.5	ns

† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance per register/driver	All outputs enabled	C _L = 0, f = 10 MHz	†	119	132	pF
		All outputs disabled		†	22	25	

† This information was not available at the time of publication.



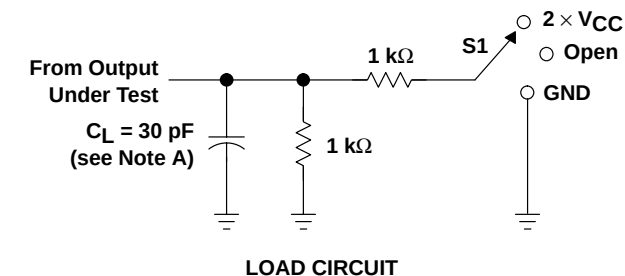
SN74ALVCH16831

1-TO-4 ADDRESS REGISTER/DRIVER

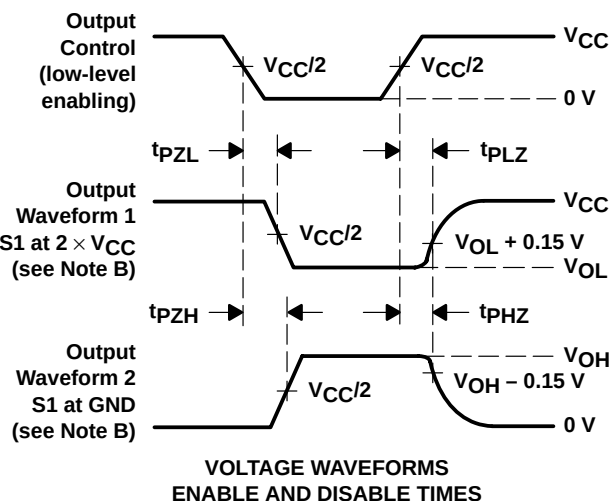
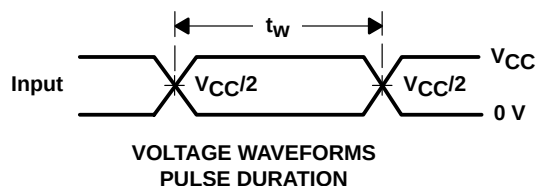
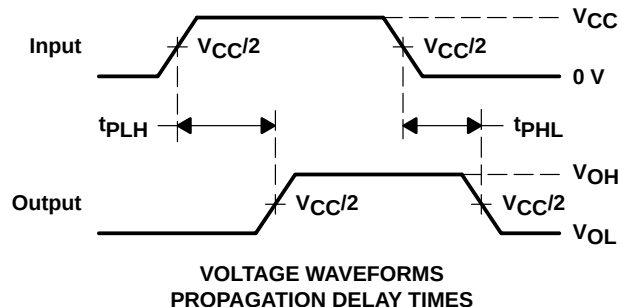
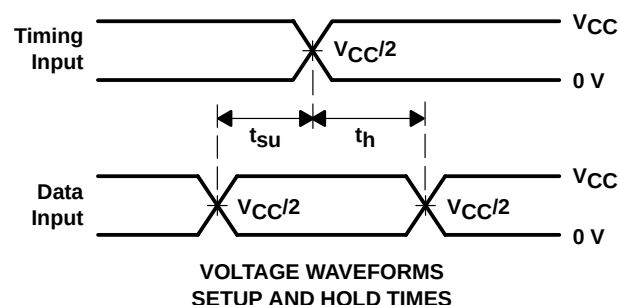
WITH 3-STATE OUTPUTS

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PARAMETER MEASUREMENT INFORMATION $V_{CC} = 1.8\text{ V}$



TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times$ V_{CC}
t_{PHZ}/t_{PZH}	GND

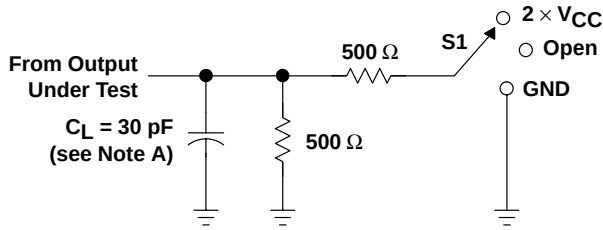


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

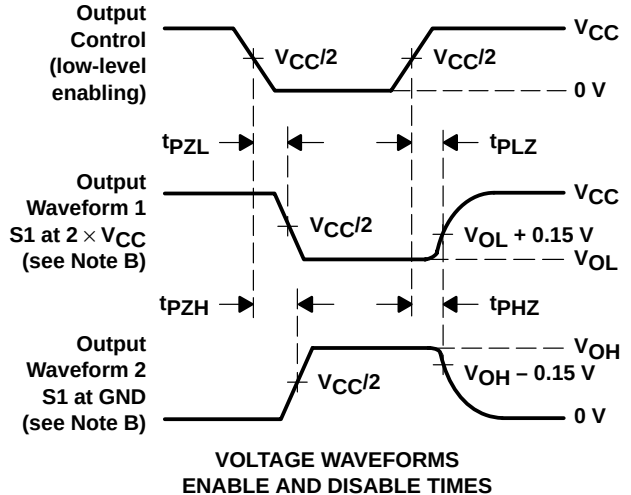
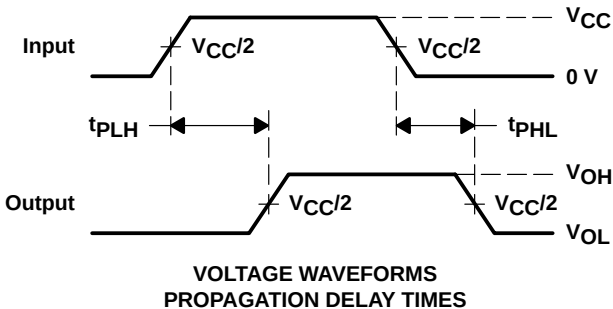
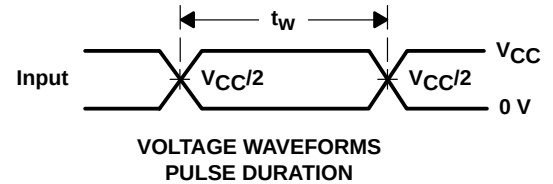
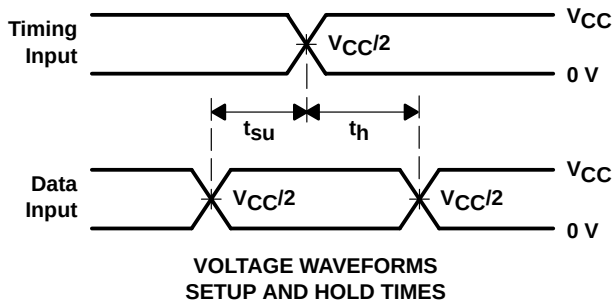
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

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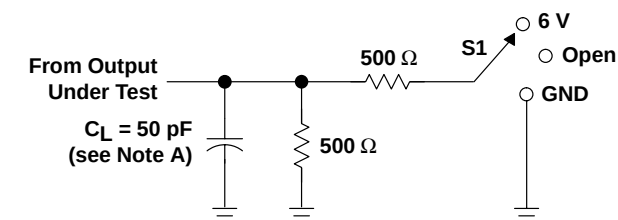
1-TO-4 ADDRESS REGISTER/DRIVER

WITH 3-STATE OUTPUTS

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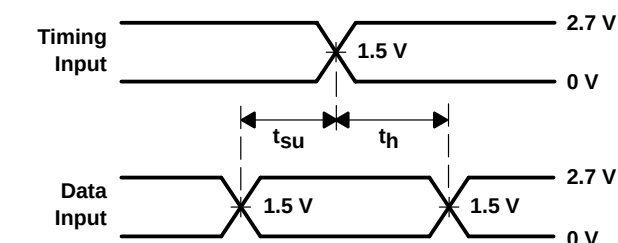
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$

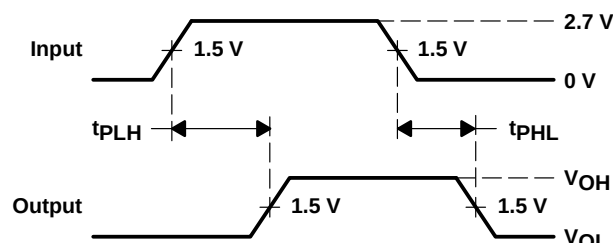


LOAD CIRCUIT

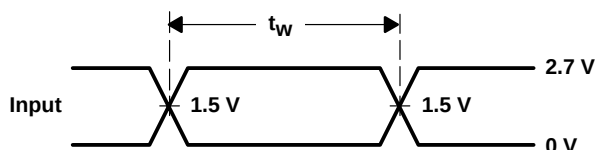
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



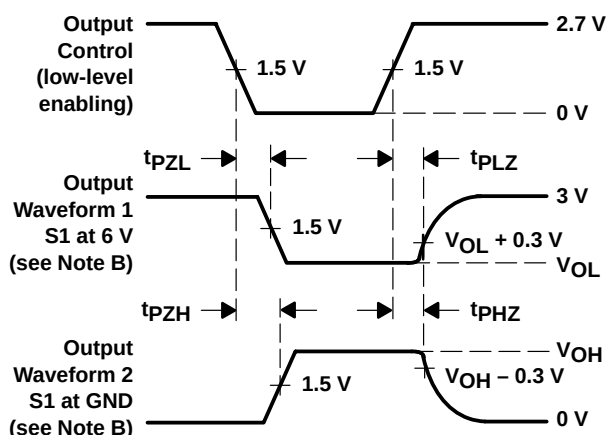
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16832 1-TO-4 ADDRESS REGISTER/DRIVER WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Packaged in Thin Shrink Small-Outline Package

description

This 1-bit to 4-bit address register/driver is designed for 1.65-V to 3.6-V V_{CC} operation. This device is ideal for use in applications in which a single address bus is driving four separate memory locations. The SN74ALVCH16832 can be used as a buffer or a register, depending on the logic level of the select ($\overline{SEL}$) input.

When $\overline{SEL}$ is a logic high, the device is in the buffer mode. The outputs follow the inputs and are controlled by the two output-enable ($\overline{OE}$) inputs. Each $\overline{OE}$ controls two groups of seven outputs.

When $\overline{SEL}$ is a logic low, the device is in the register mode. The register is an edge-triggered D-type flip-flop. On the positive transition of the clock (CLK) input, data at the A inputs is stored in the internal registers. $\overline{OE}$ operates the same as in the buffer mode.

When $\overline{OE}$ is a logic low, the outputs are in a normal logic state (high or low logic level). When $\overline{OE}$ is a logic high, the outputs are in the high-impedance state.

Neither $\overline{SEL}$ nor $\overline{OE}$ affect the internal operation of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16832 is characterized for operation from -40°C to 85°C .

DGG PACKAGE
(TOP VIEW)

4Y1	1	64	1Y2
3Y1	2	63	2Y2
GND	3	62	GND
2Y1	4	61	3Y2
1Y1	5	60	4Y2
V_{CC}	6	59	V_{CC}
A1	7	58	1Y3
GND	8	57	2Y3
A2	9	56	GND
GND	10	55	3Y3
A3	11	54	4Y3
V_{CC}	12	53	GND
NC	13	52	V_{CC}
GND	14	51	GND
CLK	15	50	1Y4
$\overline{OE1}$	16	49	2Y4
$\overline{OE2}$	17	48	3Y4
$\overline{SEL}$	18	47	4Y4
GND	19	46	GND
A4	20	45	1Y5
A5	21	44	2Y5
V_{CC}	22	43	V_{CC}
GND	23	42	3Y5
A6	24	41	4Y5
GND	25	40	GND
A7	26	39	GND
V_{CC}	27	38	V_{CC}
4Y7	28	37	1Y6
3Y7	29	36	2Y6
GND	30	35	GND
2Y7	31	34	3Y6
1Y7	32	33	4Y6

NC – No internal connection

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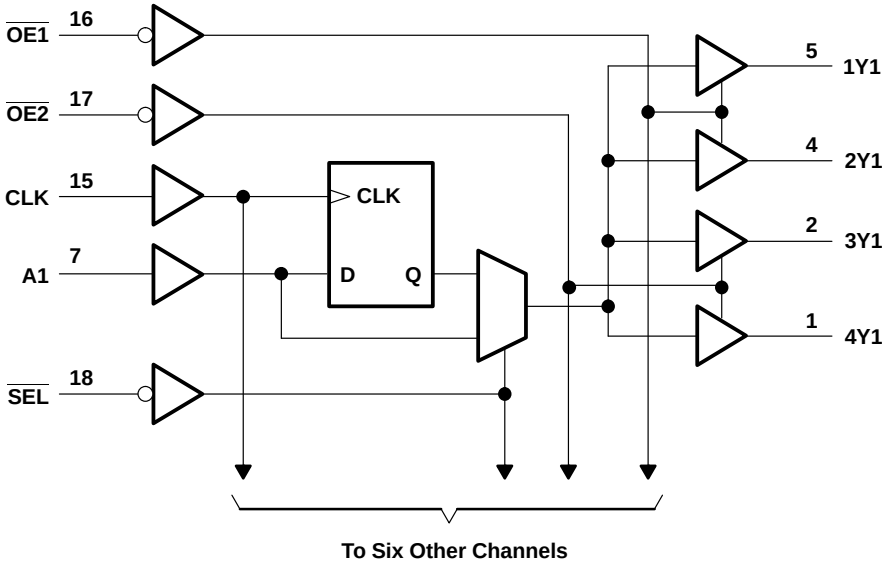
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1-TO-4 ADDRESS REGISTER/DRIVER
WITH 3-STATE OUTPUTS

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FUNCTION TABLE				
INPUTS				OUTPUT Y
OE	SEL	CLK	A	
H	X	X	X	Z
L	H	X	L	L
L	H	X	H	H
L	L	↑	L	L
L	L	↑	H	H

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	−0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	−0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	−0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	−50 mA
Output clamp current, I_{OK} ($V_O < 0$)	−50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3)	106°C/W
Storage temperature range, T_{stg}	−65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

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recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate		10		ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	3.3 V	4.5			pF
	Data inputs		5			
C _O	Outputs	3.3 V	7.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency	§		150		150		150		MHz
t _w	Pulse duration, CLK high or low	§		3.3		3.3		3.3		ns
t _{su}	Setup time, A data before CLK↑	§		2		2		1.6		ns
t _h	Hold time, A data after CLK↑	§		0.7		0.5		1.1		ns

§ This information was not available at the time of publication.



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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	A	Y		†	1.2	4	4.1		1.6	3.6	ns
	CLK			†	1.1	4.5	4.4		1.5	3.9	
	SEL			†	1.3	5.2	5.2		1.7	4.4	
t _{en}	OE	Y		†	1.1	5.1	5		1.2	4.3	ns
t _{dis}	OE	Y		†	1.4	5.5	4.7		1.6	4.5	ns

† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance per register/driver	All outputs enabled	C _L = 0, f = 10 MHz	†	119	132	pF
		All outputs disabled		†	22	25	

† This information was not available at the time of publication.

SN74ALVCH16832

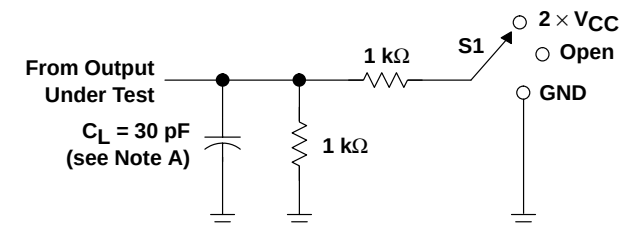
1-TO-4 ADDRESS REGISTER/DRIVER

WITH 3-STATE OUTPUTS

SCES098D – MAY 1997 – REVISED FEBRUARY 1999

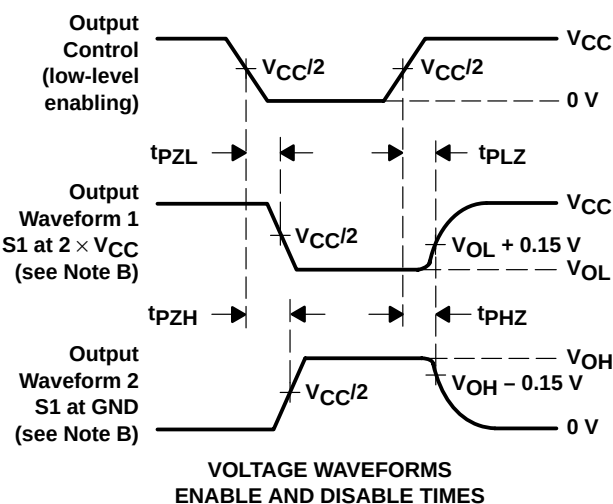
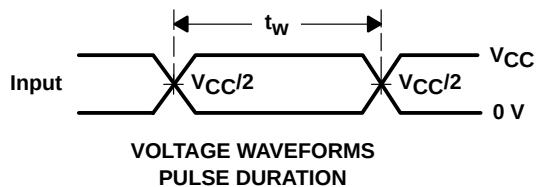
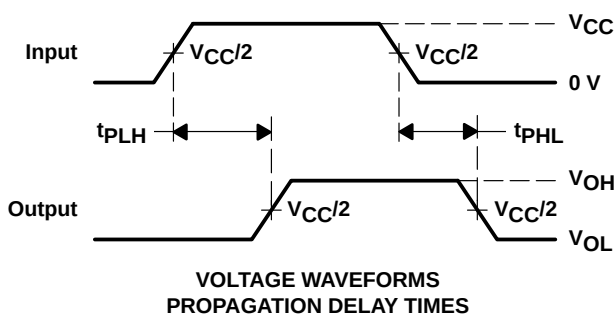
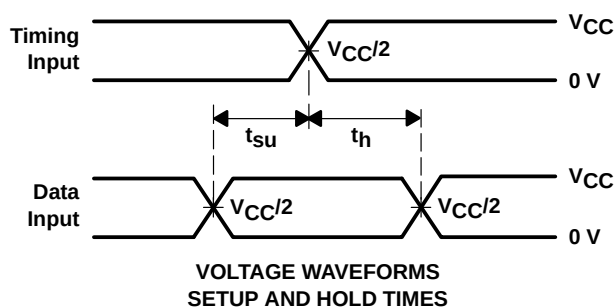
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PHL}	GND

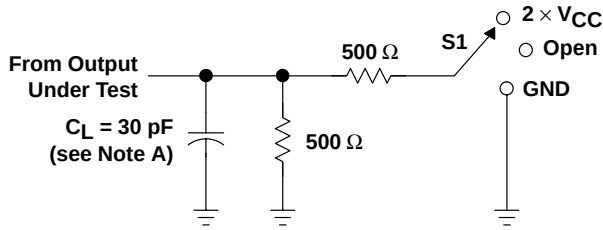


- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

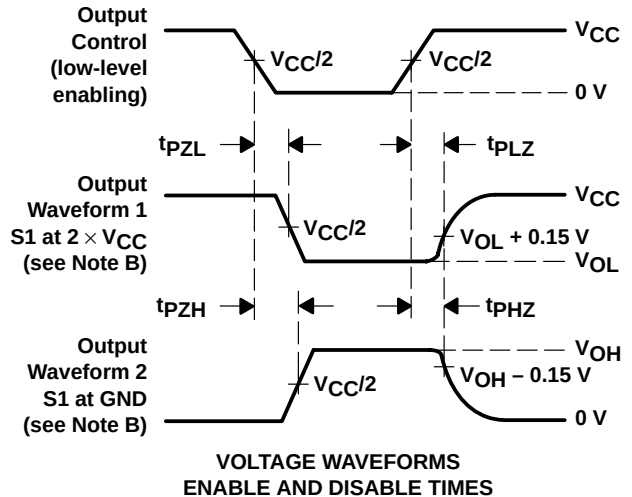
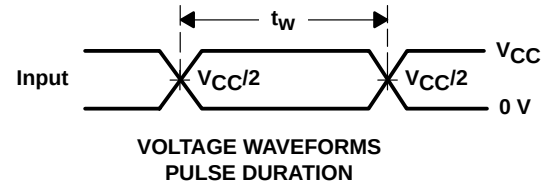
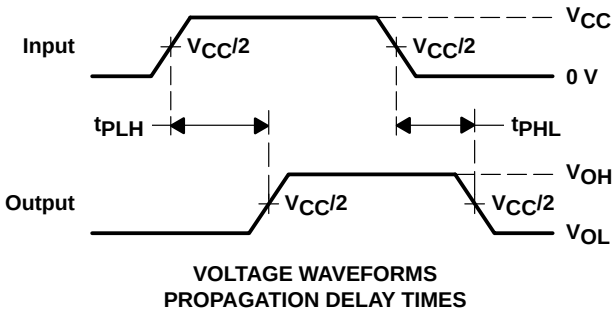
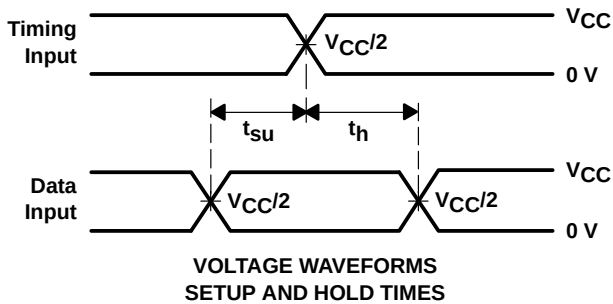
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	$2 \times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH16832

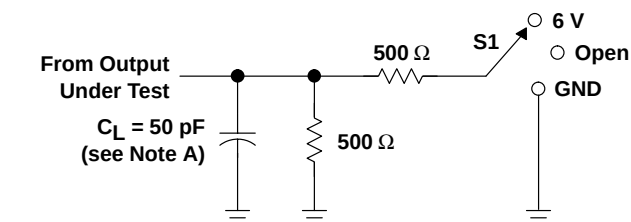
1-TO-4 ADDRESS REGISTER/DRIVER

WITH 3-STATE OUTPUTS

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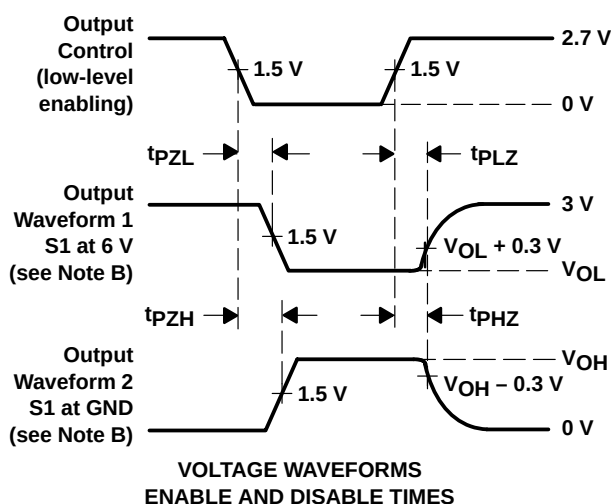
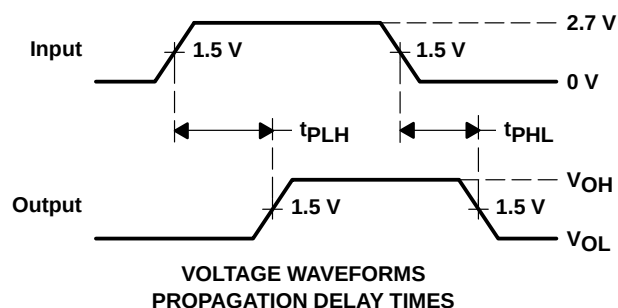
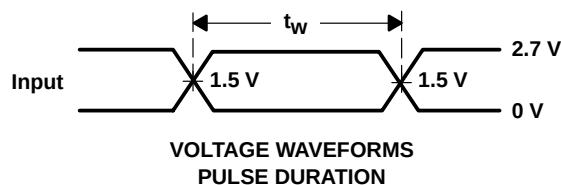
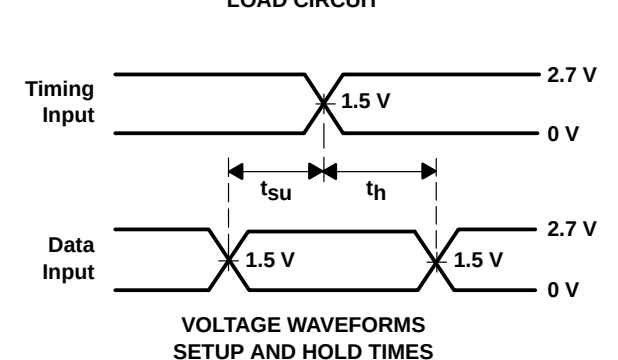
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVC16834

18-BIT UNIVERSAL BUS DRIVER WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Package Options Include Plastic Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages

description

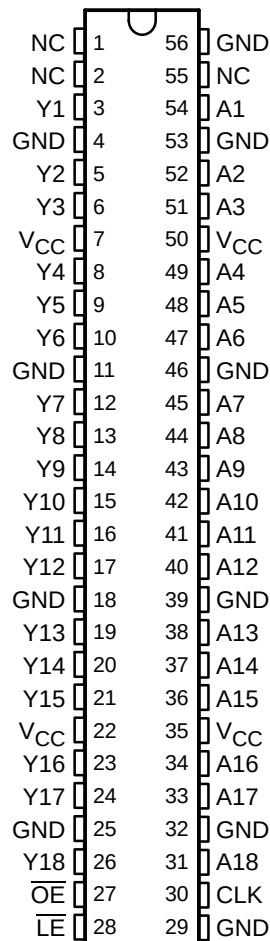
This 18-bit universal bus driver is designed for 1.65-V to 3.6-V V_{CC} operation.

Data flow from A to Y is controlled by the output-enable ($\overline{OE}$) input. The device operates in the transparent mode when the latch-enable ($\overline{LE}$) input is low. The A data is latched if the clock (CLK) input is held at a high or low logic level. If $\overline{LE}$ is high, the A data is stored in the latch/flip-flop on the low-to-high transition of CLK. When $\overline{OE}$ is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74ALVC16834 is characterized for operation from -40°C to 85°C .

DGG, DGV, OR DL PACKAGE (TOP VIEW)



NC – No internal connection

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SN74ALVC16834
18-BIT UNIVERSAL BUS DRIVER
WITH 3-STATE OUTPUTS

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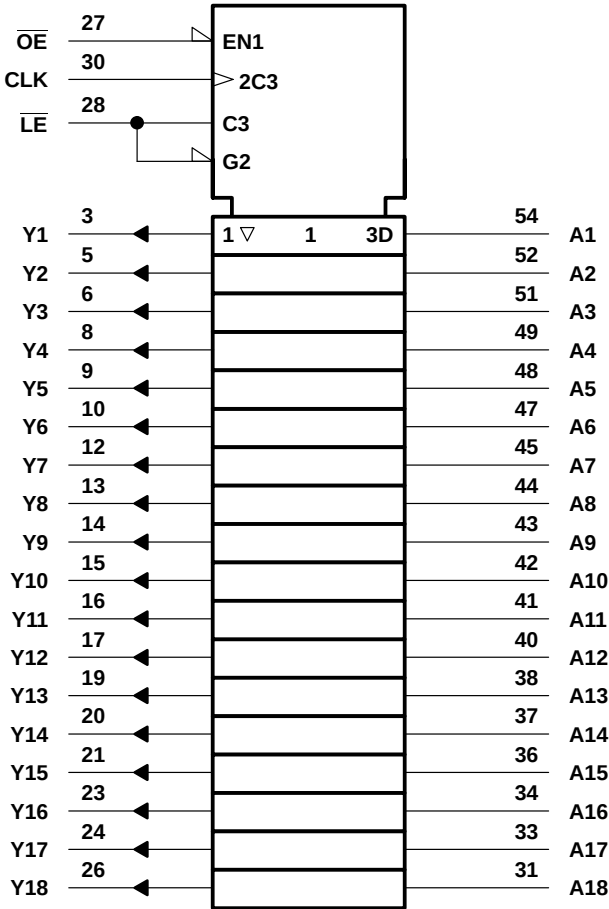
FUNCTION TABLE

INPUTS				OUTPUT Y
OE	LE	CLK	A	
H	X	X	X	Z
L	L	X	L	L
L	L	X	H	H
L	H	↑	L	L
L	H	↑	H	H
L	H	H	X	Y ₀ [†]
L	H	L	X	Y ₀ [‡]

† Output level before the indicated steady-state input conditions were established, provided that CLK is high before $\overline{LE}$ goes high

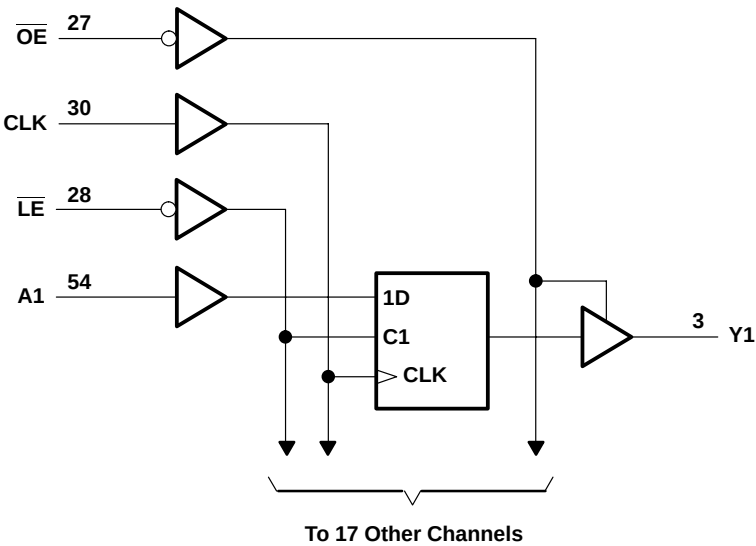
‡ Output level before the indicated steady-state input conditions were established

logic symbols



§ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC}	–0.5 V to 4.6 V
Input voltage range, V _I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V _O (see Notes 1 and 2)	–0.5 V to V _{CC} + 0.5 V
Input clamp current, I _{IK} (V _I < 0)	–50 mA
Output clamp current, I _{OK} (V _O < 0)	–50 mA
Continuous output current, I _O	±50 mA
Continuous current through each V _{CC} or GND	±100 mA
Package thermal impedance, θ _{JA} (see Note 3):	
DGG package	81°C/W
DGV package	86°C/W
DL package	74°C/W
Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

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WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65\text{ V to }1.95\text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3\text{ V to }2.7\text{ V}$	1.7	
		$V_{CC} = 2.7\text{ V to }3.6\text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65\text{ V to }1.95\text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3\text{ V to }2.7\text{ V}$	0.7	
		$V_{CC} = 2.7\text{ V to }3.6\text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65\text{ V}$	–4	mA
		$V_{CC} = 2.3\text{ V}$	–12	
		$V_{CC} = 2.7\text{ V}$	–12	
		$V_{CC} = 3\text{ V}$	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65\text{ V}$	4	mA
		$V_{CC} = 2.3\text{ V}$	12	
		$V_{CC} = 2.7\text{ V}$	12	
		$V_{CC} = 3\text{ V}$	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
		I _{OL} = 12 mA	2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	4			pF
	Data inputs			5.5			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

				V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
				MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency			‡		150		150		150		MHz
t _w	Pulse duration	LE low		‡		3.3		3.3		3.3		ns
		CLK high or low		‡		3.3		3.3		3.3		
t _{su}	Setup time	Data before CLK↑		‡		2.1		2.1		1.7		ns
		Data before LE↑	CLK high	‡		2.2		2.3		1.9		
			CLK low	‡		1.5		1.9		1.5		
t _h	Hold time	Data after CLK↑		‡		0.6		0.6		0.7		ns
		Data after LE↑	CLK high or low	‡		0.8		0.8		0.9		

‡ This information was not available at the time of publication.



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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	A	Y	†		1 4.4		4.2		1 3.6		ns
	$\overline{\text{LE}}$		†		1.3 6		5.9		1.5 4.9		
	CLK		†		1.2 6		5.3		1.5 4.6		
t _{en}	$\overline{\text{OE}}$	Y	†		1.4 5.6		5.6		1.5 5		ns
t _{dis}	$\overline{\text{OE}}$	Y	†		1 4		4.7		1.8 4.5		ns

† This information was not available at the time of publication.

switching characteristics from 0°C to 65°C, C_L = 50 pF

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 3.3 V ± 0.15 V		UNIT
			MIN	MAX	
t _{pd}	CLK	Y	1.7	4.3	ns

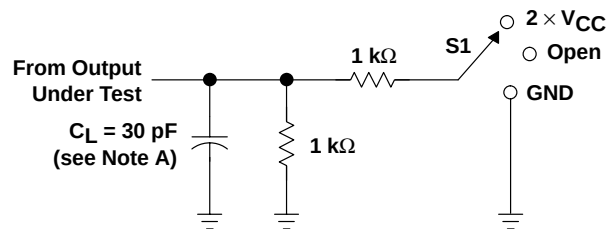
operating characteristics, T_A = 25°C

PARAMETER		TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
			TYP	TYP	TYP	
C _{pd} Power dissipation capacitance	Outputs enabled	C _L = 0, f = 10 MHz	†	38	41	pF
	Outputs disabled		†	13	15	

† This information was not available at the time of publication.

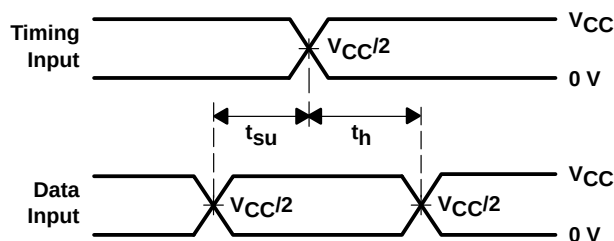
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$

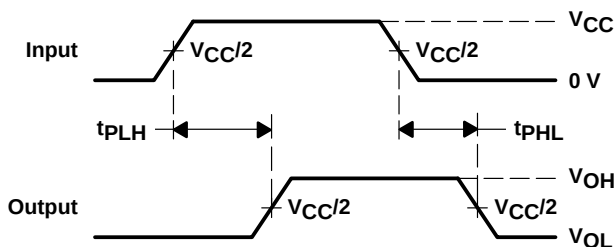


LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PHZ}	GND



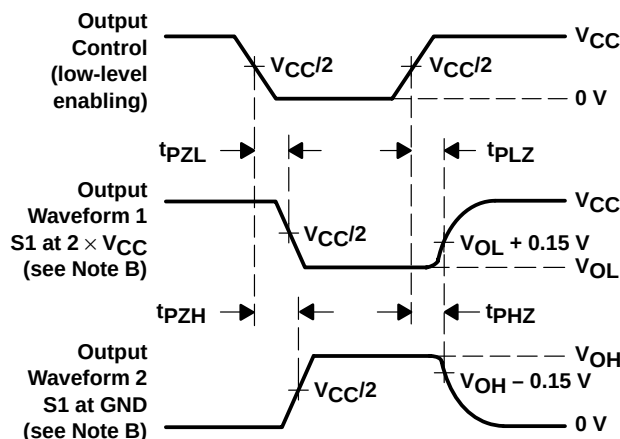
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVC16834

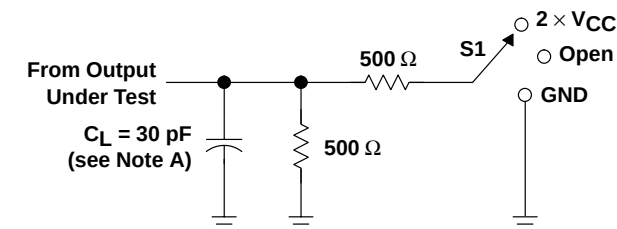
18-BIT UNIVERSAL BUS DRIVER

WITH 3-STATE OUTPUTS

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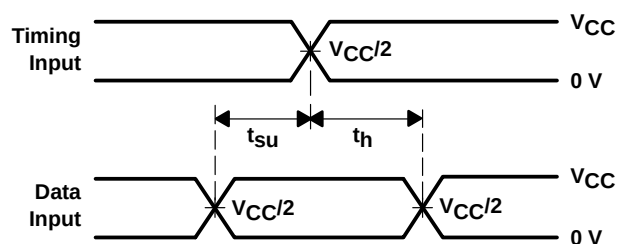
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

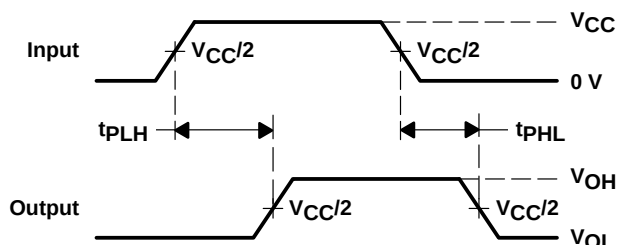


LOAD CIRCUIT

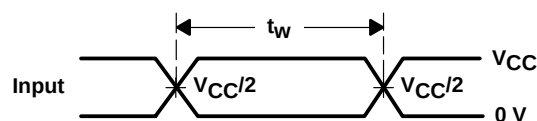
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



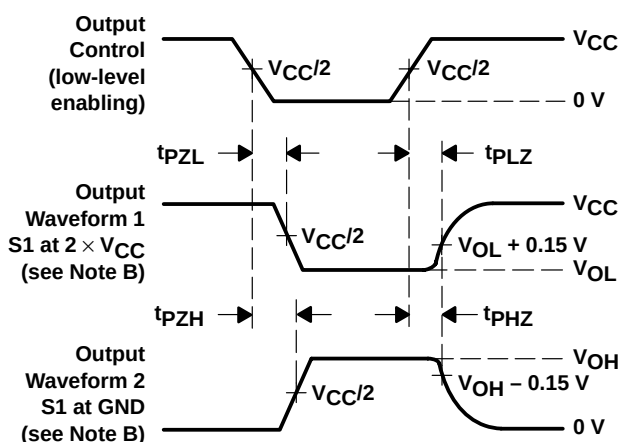
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



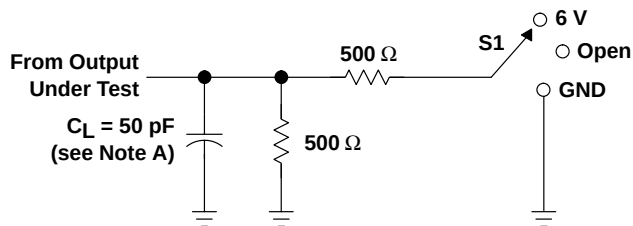
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

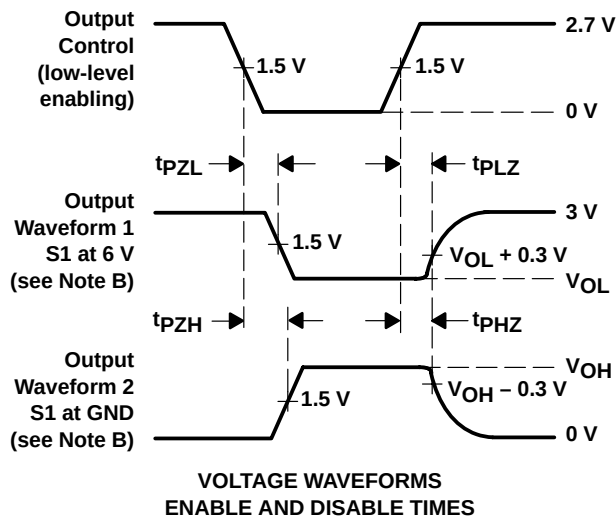
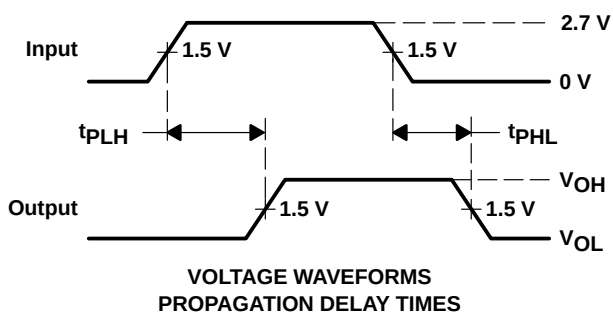
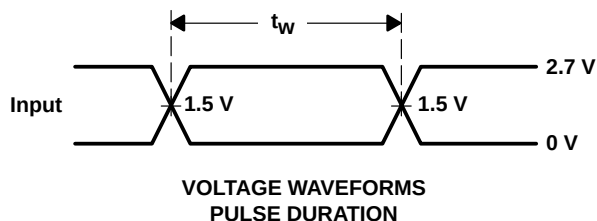
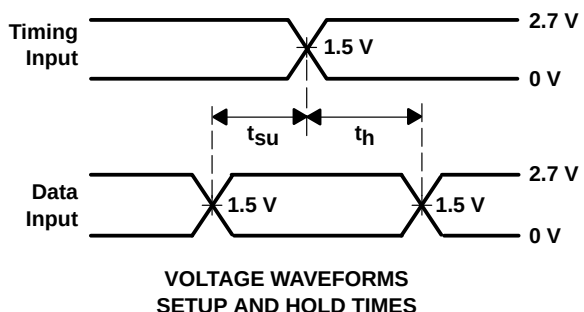
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages

description

This 18-bit universal bus driver is designed for 1.65-V to 3.6-V V_{CC} operation.

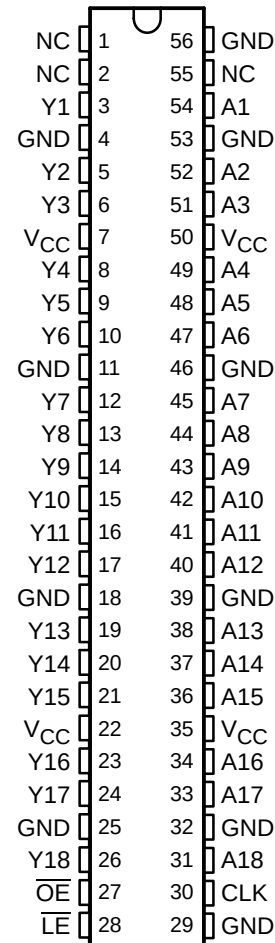
Data flow from A to Y is controlled by the output-enable ($\overline{OE}$) input. The device operates in the transparent mode when the latch-enable ($\overline{LE}$) input is low. The A data is latched if the clock (CLK) input is held at a high or low logic level. If $\overline{LE}$ is high, the A data is stored in the latch/flip-flop on the low-to-high transition of CLK. When $\overline{OE}$ is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16834 is characterized for operation from -40°C to 85°C .

DGG, DGV, OR DL PACKAGE
(TOP VIEW)



NC – No internal connection

PRODUCT PREVIEW

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SN74ALVCH16834
18-BIT UNIVERSAL BUS DRIVER
WITH 3-STATE OUTPUTS

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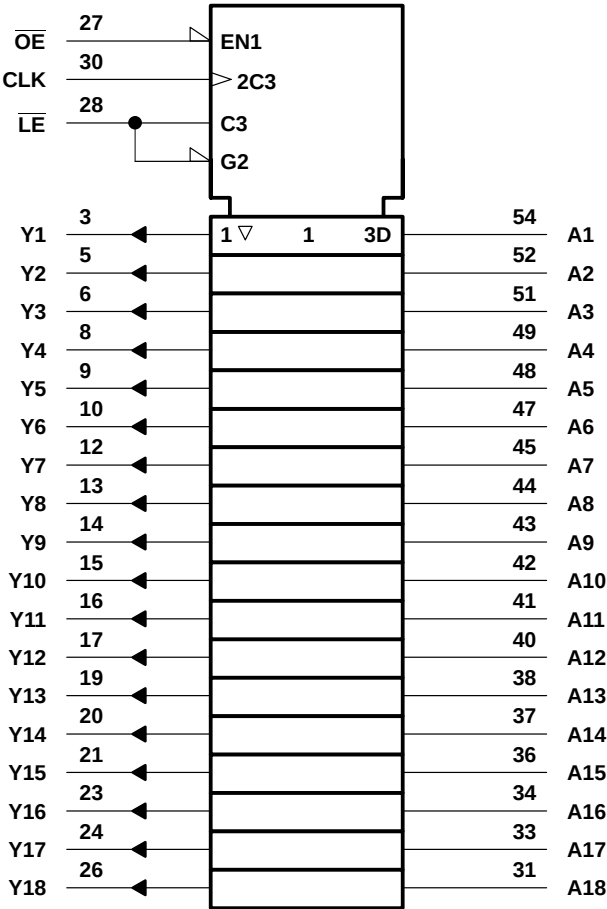
FUNCTION TABLE

INPUTS				OUTPUT Y
OE	LE	CLK	A	
H	X	X	X	Z
L	L	X	L	L
L	L	X	H	H
L	H	↑	L	L
L	H	↑	H	H
L	H	H	X	Y ₀ [†]
L	H	L	X	Y ₀ [‡]

† Output level before the indicated steady-state input conditions were established, provided that CLK is high before LE goes high

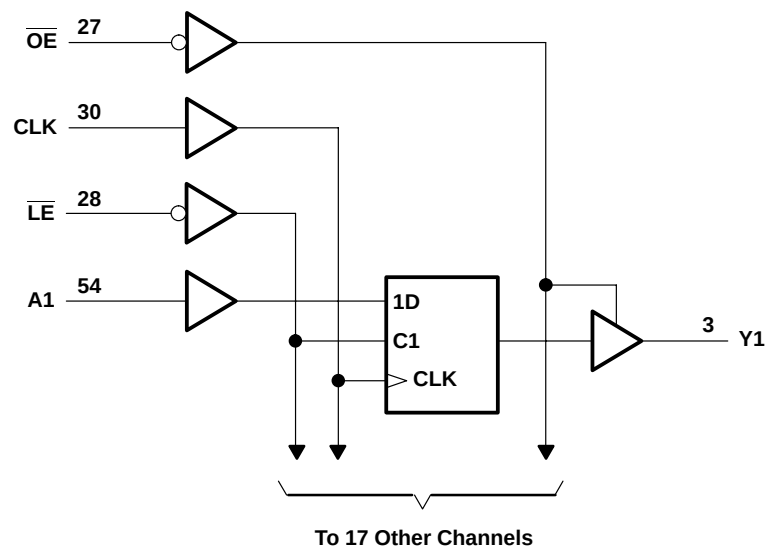
‡ Output level before the indicated steady-state input conditions were established

logic symbols



§ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3):	
DGG package	81°C/W
DGV package	86°C/W
DL package	74°C/W
Storage temperature range, T_{Stg}	–65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
- The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 - This value is limited to 4.6 V maximum.
 - The package thermal impedance is calculated in accordance with JESD 51.

PRODUCT PREVIEW

SN74ALVCH16834 18-BIT UNIVERSAL BUS DRIVER WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–4	mA
		$V_{CC} = 2.3 \text{ V}$	–12	
		$V_{CC} = 2.7 \text{ V}$	–12	
		$V_{CC} = 3 \text{ V}$	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	4	mA
		$V_{CC} = 2.3 \text{ V}$	12	
		$V_{CC} = 2.7 \text{ V}$	12	
		$V_{CC} = 3 \text{ V}$	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V			pF
	Data inputs					
C _O	Outputs	V _O = V _{CC} or GND	3.3 V			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency									MHz
t _w	Pulse duration	LE low								ns
		CLK high or low								
t _{su}	Setup time	Data before CLK↑								ns
		Data before LE↑	CLK high							
			CLK low							
t _h	Hold time	Data after CLK↑								ns
		Data after LE↑	CLK high or low							

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18-BIT UNIVERSAL BUS DRIVER

WITH 3-STATE OUTPUTS

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}											MHz
t _{pd}	A	Y									ns
	$\overline{LE}$										
	CLK										
t _{en}	$\overline{OE}$	Y									ns
t _{dis}	$\overline{OE}$	Y									ns

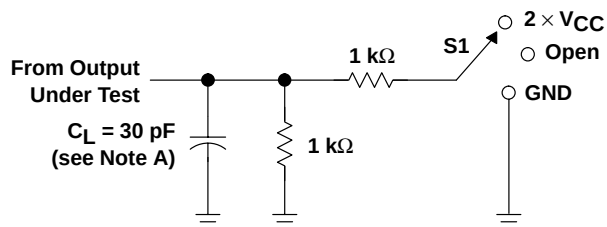
switching characteristics from 0°C to 65°C, C_L = 50 pF

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 3.3 V ± 0.15 V		UNIT
			MIN	MAX	
t _{pd}	CLK	Y			ns

operating characteristics, T_A = 25°C

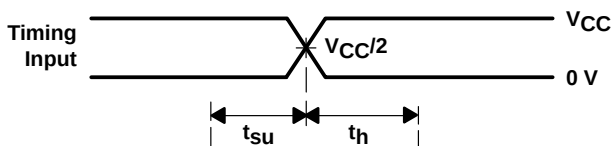
PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 0, f = 10 MHz				pF
		Outputs disabled					

PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8\text{ V}$

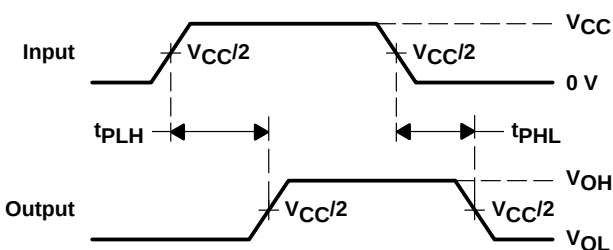


LOAD CIRCUIT

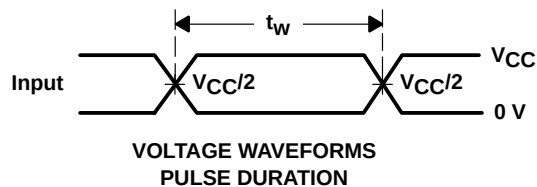
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



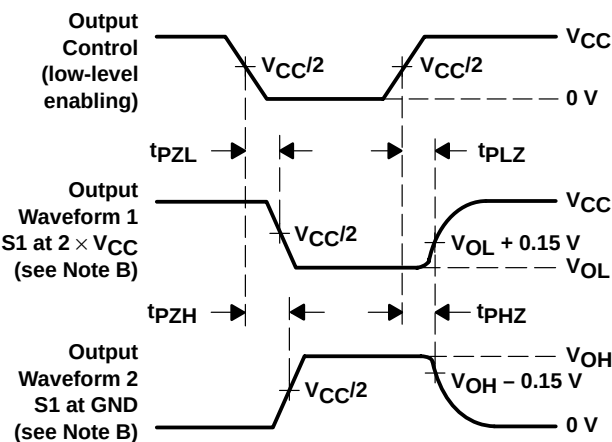
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

PRODUCT PREVIEW

SN74ALVCH16834

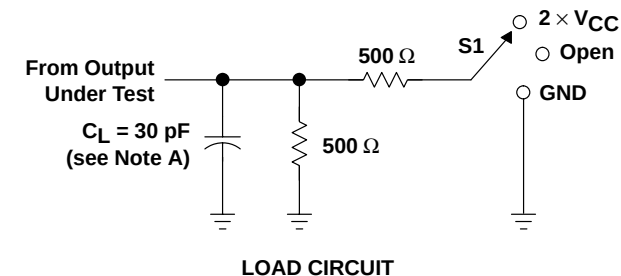
18-BIT UNIVERSAL BUS DRIVER

WITH 3-STATE OUTPUTS

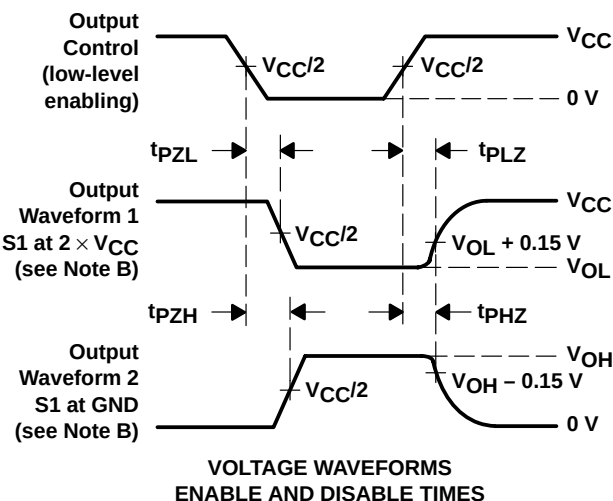
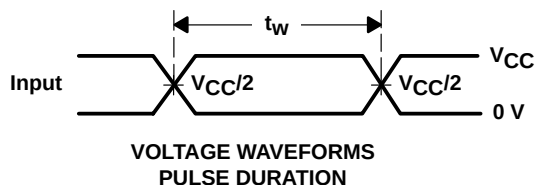
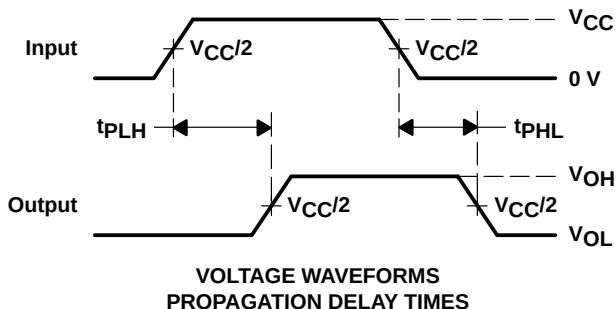
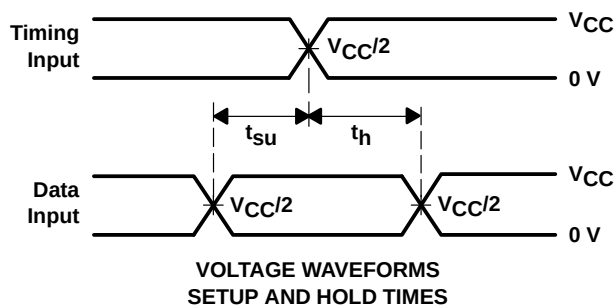
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PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$



TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND

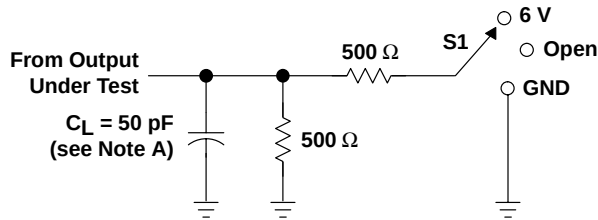


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

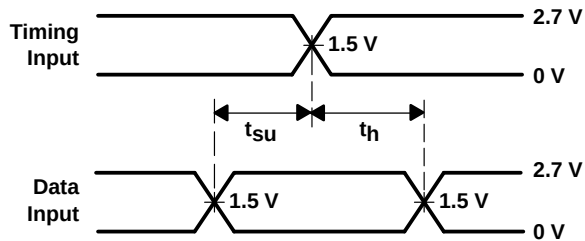
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

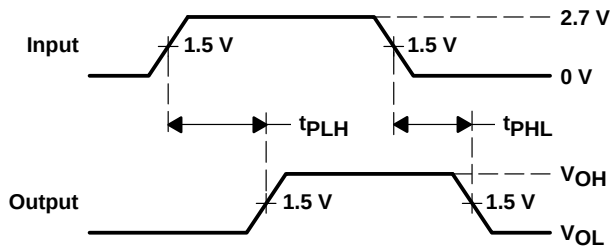


LOAD CIRCUIT

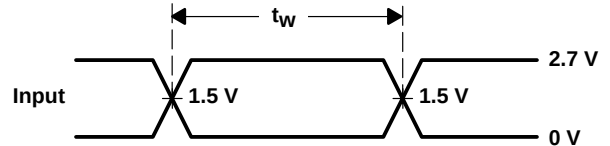
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



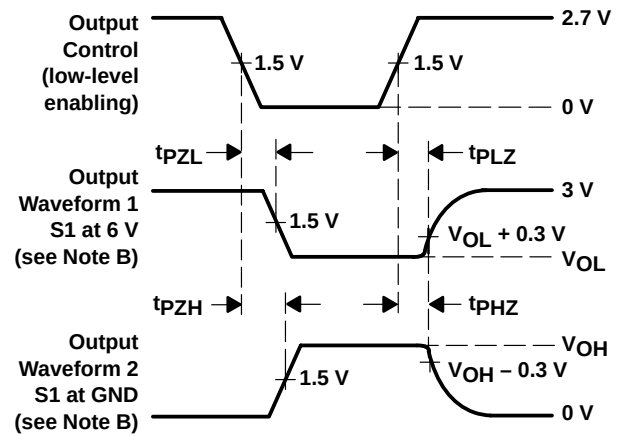
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

PRODUCT PREVIEW

SN74ALVC16835

18-BIT UNIVERSAL BUS DRIVER WITH 3-STATE OUTPUTS

SCES125D – FEBRUARY 1998 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Ideal for Use in PC100 Register DIMM Revision 1.1
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Package Options Include Plastic Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages

description

This 18-bit universal bus driver is designed for 1.65-V to 3.6-V V_{CC} operation.

Data flow from A to Y is controlled by the output-enable ($\overline{OE}$) input. The device operates in the transparent mode when the latch-enable (LE) input is high. The A data is latched if the clock (CLK) input is held at a high or low logic level. If LE is low, the A data is stored in the latch/flip-flop on the low-to-high transition of CLK. When $\overline{OE}$ is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74ALVC16835 is characterized for operation from -40°C to 85°C .

DGG, DGV, OR DL PACKAGE (TOP VIEW)

NC	1	56	GND
NC	2	55	NC
Y1	3	54	A1
GND	4	53	GND
Y2	5	52	A2
Y3	6	51	A3
V_{CC}	7	50	V_{CC}
Y4	8	49	A4
Y5	9	48	A5
Y6	10	47	A6
GND	11	46	GND
Y7	12	45	A7
Y8	13	44	A8
Y9	14	43	A9
Y10	15	42	A10
Y11	16	41	A11
Y12	17	40	A12
GND	18	39	GND
Y13	19	38	A13
Y14	20	37	A14
Y15	21	36	A15
V_{CC}	22	35	V_{CC}
Y16	23	34	A16
Y17	24	33	A17
GND	25	32	GND
Y18	26	31	A18
$\overline{OE}$	27	30	CLK
LE	28	29	GND

NC – No internal connection

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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SN74ALVC16835
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WITH 3-STATE OUTPUTS

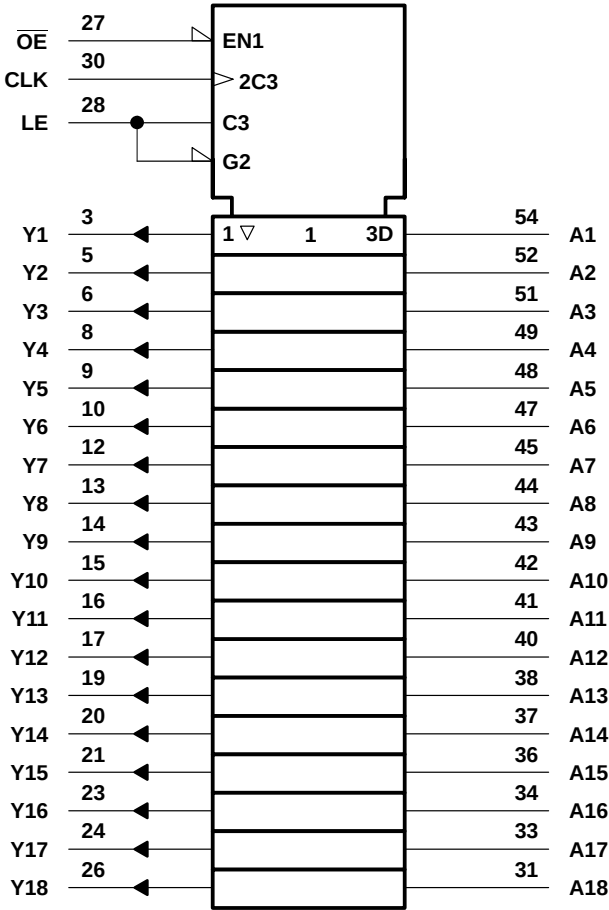
SCES125D – FEBRUARY 1998 – REVISED FEBRUARY 1999

FUNCTION TABLE

INPUTS				OUTPUT Y
OE	LE	CLK	A	
H	X	X	X	Z
L	H	X	L	L
L	H	X	H	H
L	L	↑	L	L
L	L	↑	H	H
L	L	L or H	X	Y ₀ [†]

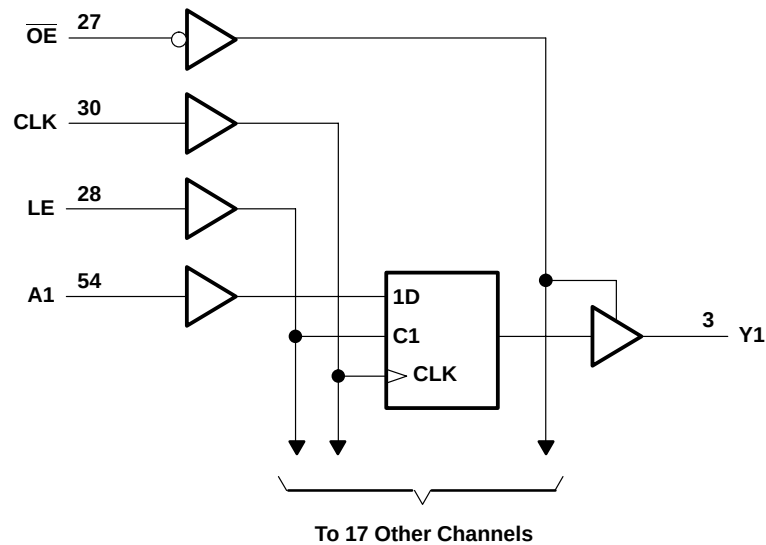
† Output level before the indicated steady-state input conditions were established, provided that CLK is high before LE goes low

logic symbol‡



‡ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3):	
DGG package	81°C/W
DGV package	86°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

SN74ALVC16835
18-BIT UNIVERSAL BUS DRIVER
WITH 3-STATE OUTPUTS

SCES125D – FEBRUARY 1998 – REVISED FEBRUARY 1999

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–4	mA
		$V_{CC} = 2.3 \text{ V}$	–12	
		$V_{CC} = 2.7 \text{ V}$	–12	
		$V_{CC} = 3 \text{ V}$	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	4	mA
		$V_{CC} = 2.3 \text{ V}$	12	
		$V_{CC} = 2.7 \text{ V}$	12	
		$V_{CC} = 3 \text{ V}$	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
		I _{OL} = 12 mA	2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3.5			pF
	Data inputs			5			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

				V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
				MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency			‡		150		150		150		MHz
t _w	Pulse duration	LE high		‡		3.3		3.3		3.3		ns
		CLK high or low		‡		3.3		3.3		3.3		
t _{su}	Setup time	Data before CLK↑		‡		2.2		2.1		1.7		ns
		Data before LE↓	CLK high	‡		1.9		1.6		1.5		
			CLK low	‡		1.3		1.1		1		
t _h	Hold time	Data after CLK↑		‡		0.6		0.6		0.7		ns
		Data after LE↓	CLK high or low	‡		1.4		1.7		1.4		

‡ This information was not available at the time of publication.



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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	A	Y		†	1	4.2		4.2	1	3.6	ns
	LE			†	1.3	5		4.9	1.3	4.2	
	CLK			†	1.4	5.5		5.2	1.4	4.5	
t _{en}	OE	Y		†	1.4	5.5		5.6	1.1	4.6	ns
t _{dis}	OE	Y		†	1	4.5		4.3	1.3	3.9	ns

† This information was not available at the time of publication.

switching characteristics from 0°C to 85°C, C_L = 0 pF

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 3.3 V ± 0.15 V		UNIT
			MIN	MAX	
t _{pd} †	A	Y	0.9	2	ns
	CLK	Y	1.5	2.9	

† Texas Instruments SPICE simulation data

switching characteristics from 0°C to 65°C, C_L = 50 pF

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 3.3 V ± 0.15 V		UNIT
			MIN	MAX	
t _{pd}	A	Y	1	4	ns
	CLK	Y	1.7	4.5	

operating characteristics, T_A = 25°C

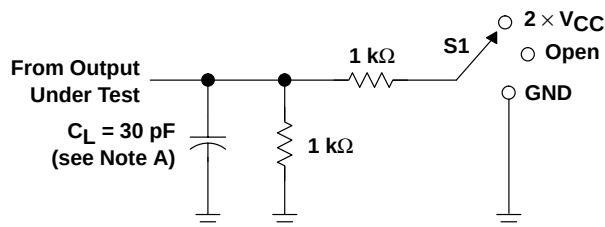
PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd} Power dissipation capacitance	Outputs enabled	C _L = 0, f = 10 MHz		†	26	31	pF
	Outputs disabled			†	12	14	

† This information was not available at the time of publication.



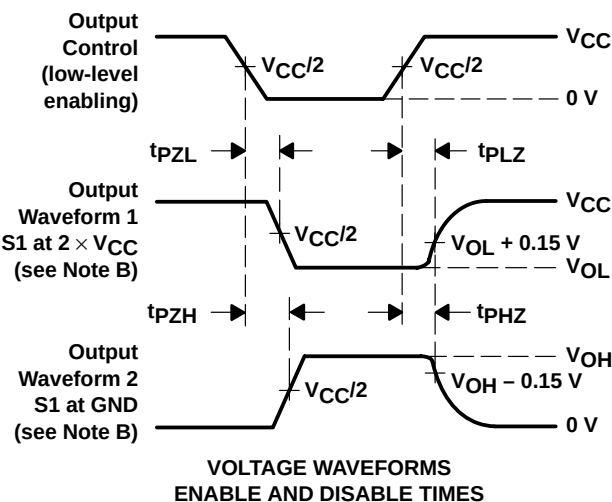
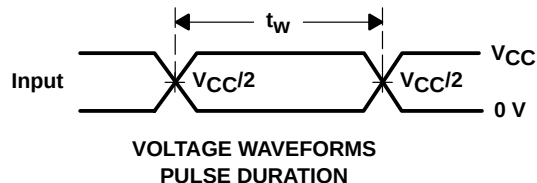
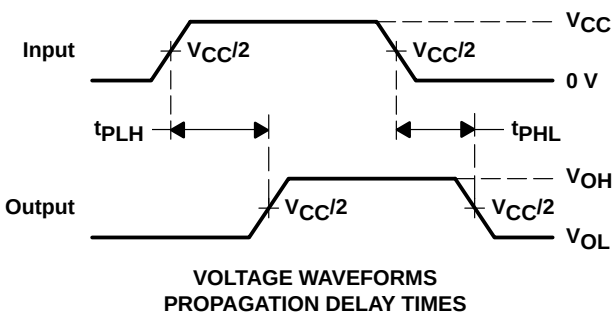
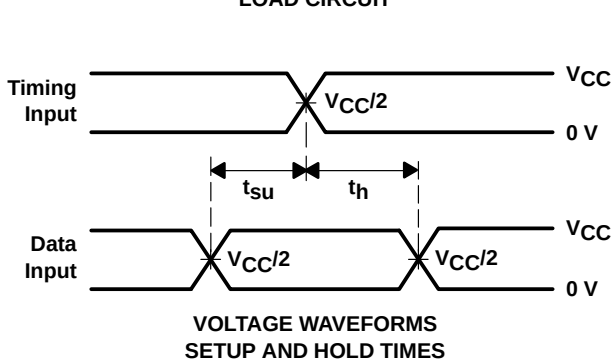
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

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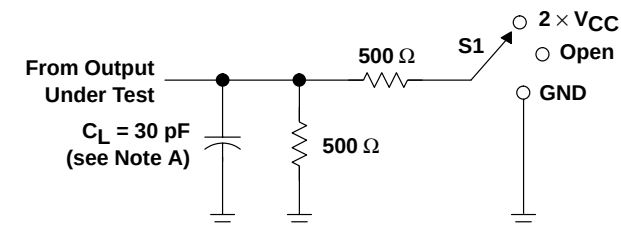
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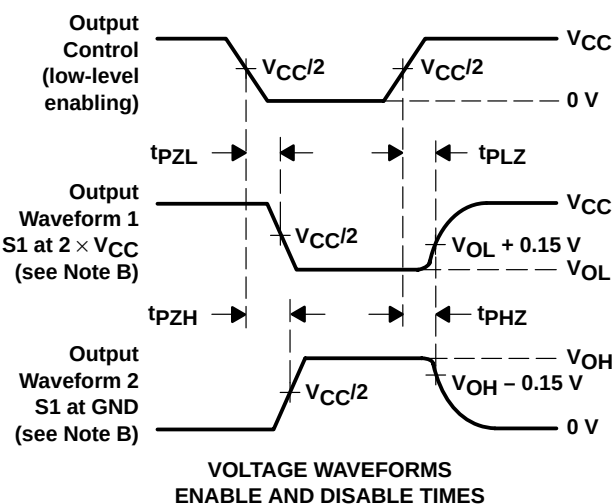
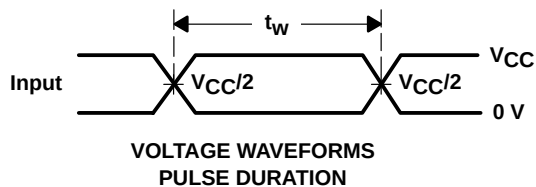
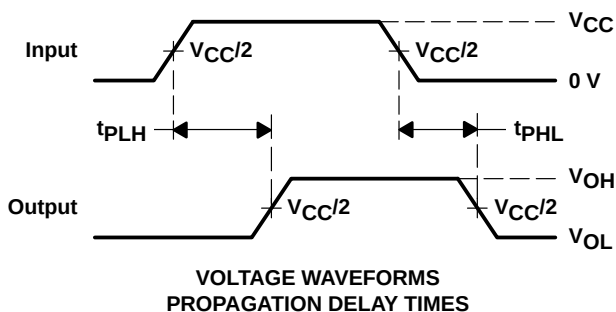
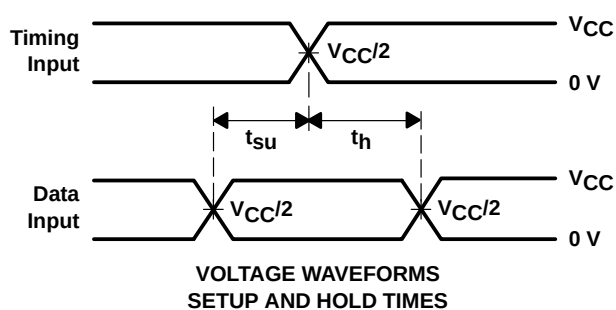
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PHL}	GND

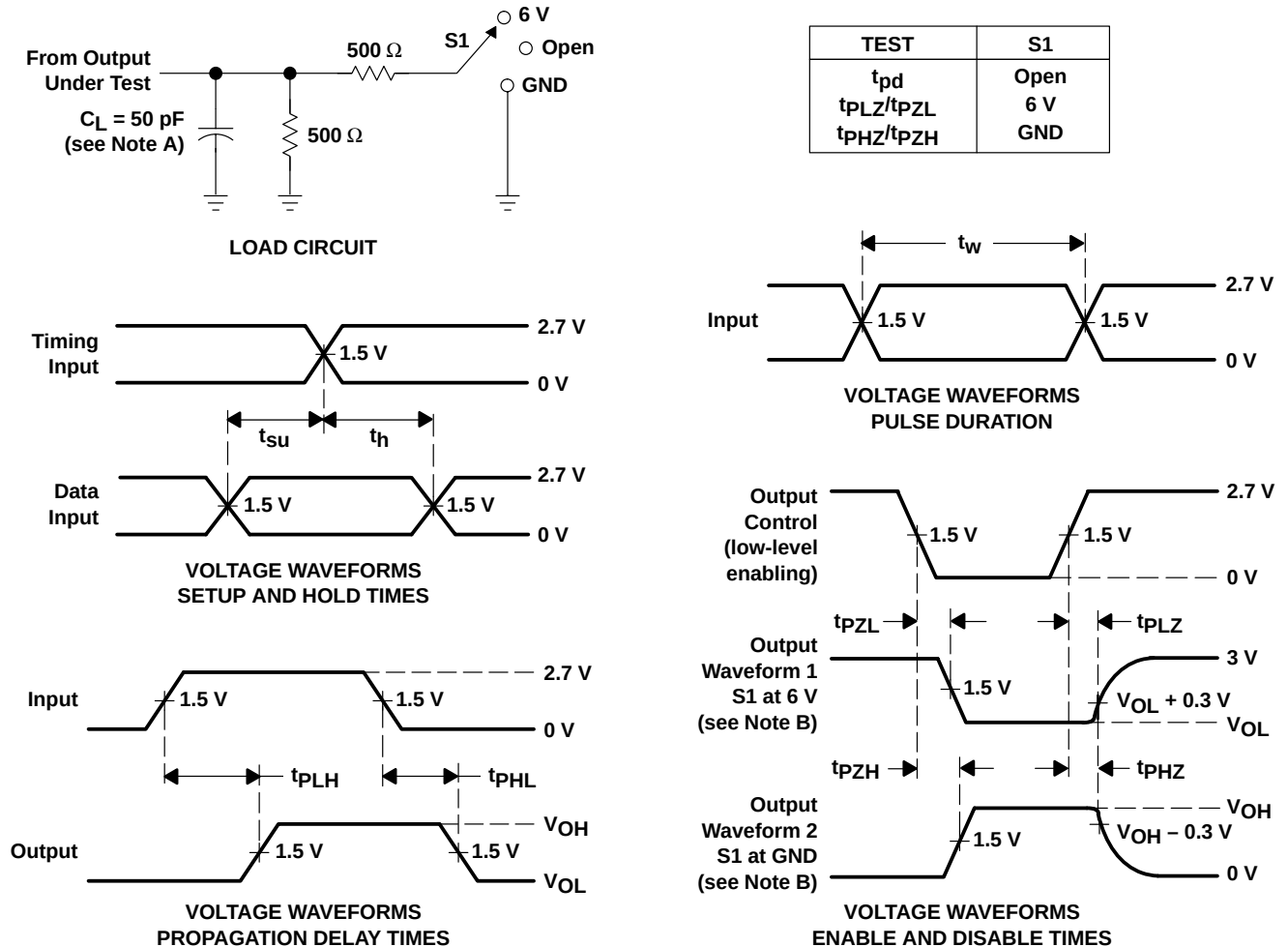


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

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TYPICAL CHARACTERISTICS

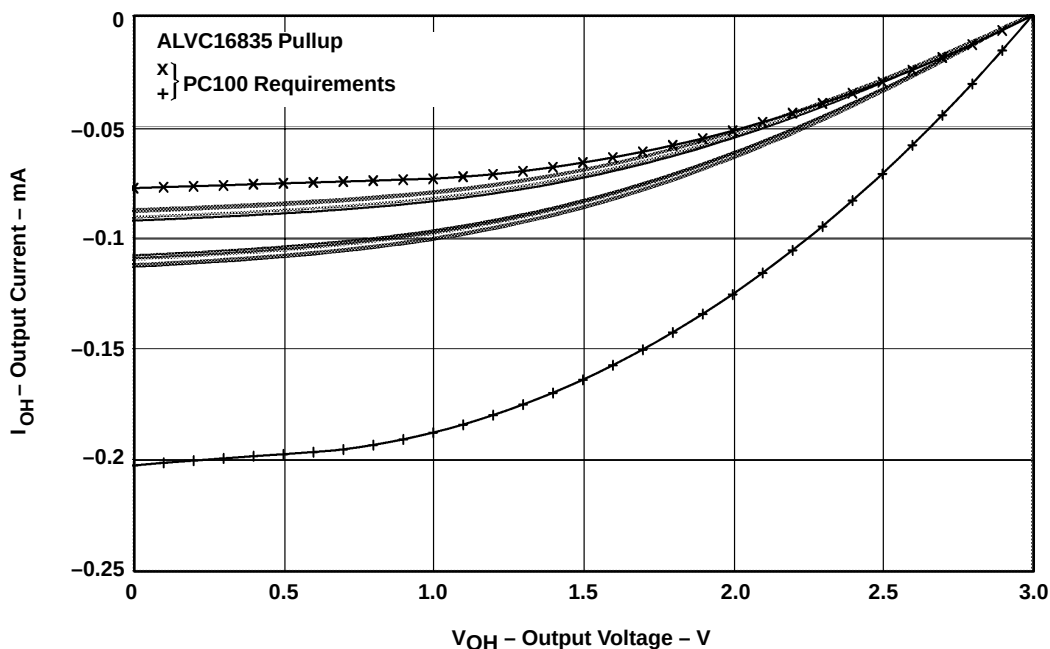


Figure 4. IV Characteristics – Pullup

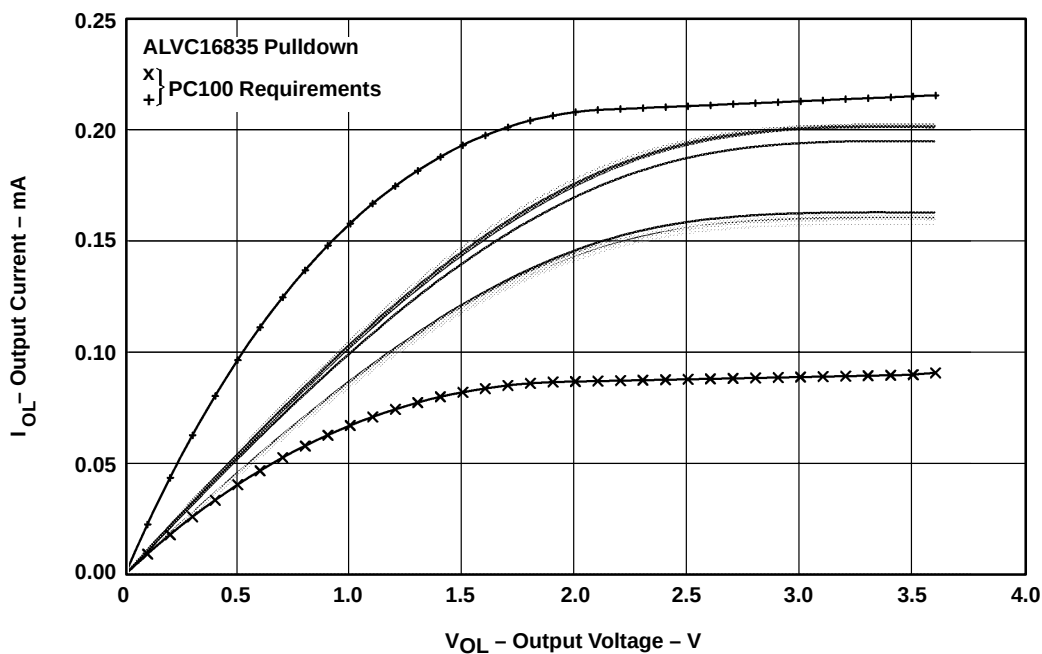


Figure 5. IV Characteristics – Pulldown



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- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages

description

This 18-bit universal bus driver is designed for 1.65-V to 3.6-V V_{CC} operation.

Data flow from A to Y is controlled by the output-enable ($\overline{OE}$) input. The device operates in the transparent mode when the latch-enable (LE) input is high. The A data is latched if the clock (CLK) input is held at a high or low logic level. If LE is low, the A data is stored in the latch/flip-flop on the low-to-high transition of CLK. When $\overline{OE}$ is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16835 is characterized for operation from -40°C to 85°C .

DGG, DGV, OR DL PACKAGE (TOP VIEW)

NC	1	56	GND
NC	2	55	NC
Y1	3	54	A1
GND	4	53	GND
Y2	5	52	A2
Y3	6	51	A3
V_{CC}	7	50	V_{CC}
Y4	8	49	A4
Y5	9	48	A5
Y6	10	47	A6
GND	11	46	GND
Y7	12	45	A7
Y8	13	44	A8
Y9	14	43	A9
Y10	15	42	A10
Y11	16	41	A11
Y12	17	40	A12
GND	18	39	GND
Y13	19	38	A13
Y14	20	37	A14
Y15	21	36	A15
V_{CC}	22	35	V_{CC}
Y16	23	34	A16
Y17	24	33	A17
GND	25	32	GND
Y18	26	31	A18
$\overline{OE}$	27	30	CLK
LE	28	29	GND

NC – No internal connection

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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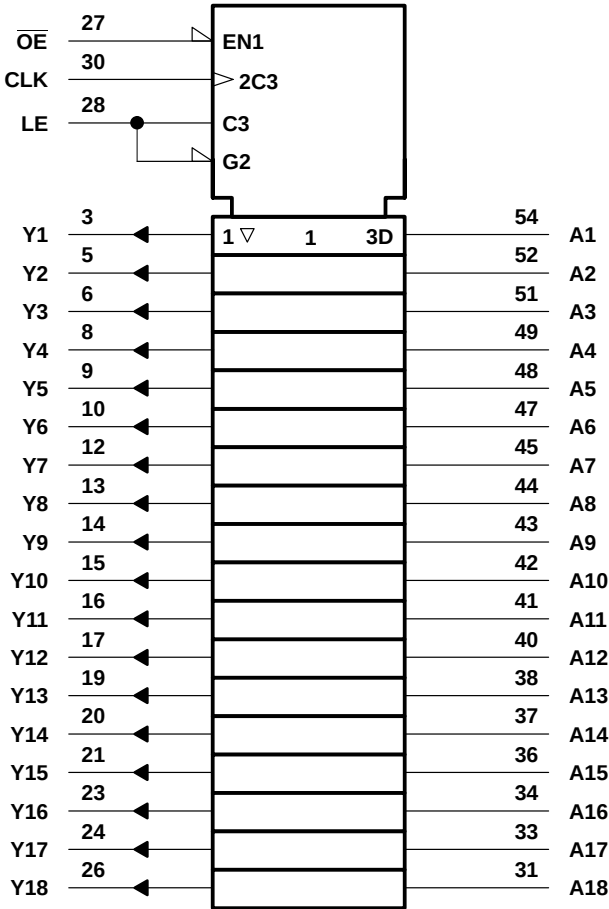
FUNCTION TABLE

INPUTS				OUTPUT Y
OE	LE	CLK	A	
H	X	X	X	Z
L	H	X	L	L
L	H	X	H	H
L	L	↑	L	L
L	L	↑	H	H
L	L	H	X	Y ₀ [†]
L	L	L	X	Y ₀ [‡]

† Output level before the indicated steady-state input conditions were established, provided that CLK is high before LE goes low

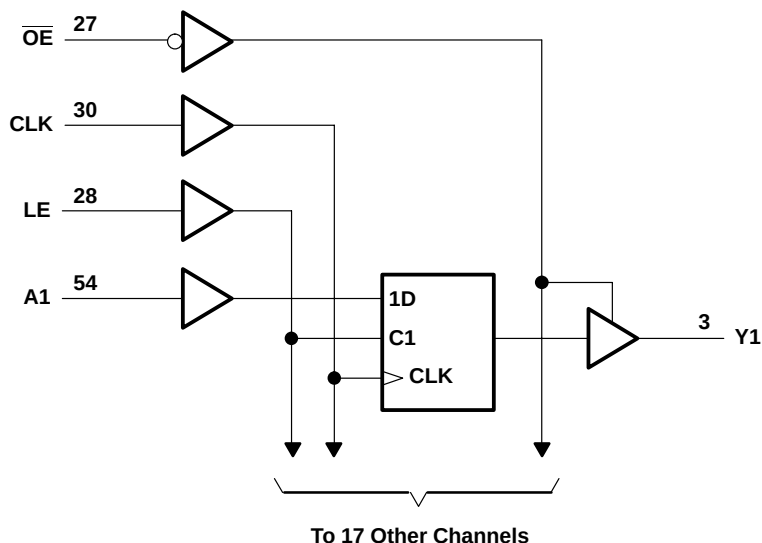
‡ Output level before the indicated steady-state input conditions were established

logic symbols



§ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3):	
DGG package	81°C/W
DGV package	86°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–4	mA
		$V_{CC} = 2.3 \text{ V}$	–12	
		$V_{CC} = 2.7 \text{ V}$	–12	
		$V_{CC} = 3 \text{ V}$	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	4	mA
		$V_{CC} = 2.3 \text{ V}$	12	
		$V_{CC} = 2.7 \text{ V}$	12	
		$V_{CC} = 3 \text{ V}$	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
		I _{OL} = 12 mA	2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3.5			pF
	Data inputs			6			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

				V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
				MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency			§		150		150		150		MHz
t _w	Pulse duration	LE high		§		3.3		3.3		3.3		ns
		CLK high or low		§		3.3		3.3		3.3		
t _{su}	Setup time	Data before CLK↑		§		2.2		2.1		1.7		ns
		Data before LE↓	CLK high	§		1.9		1.6		1.5		
			CLK low	§		1.3		1.1		1		
t _h	Hold time	Data after CLK↑		§		0.6		0.6		0.7		ns
		Data after LE↓	CLK high or low		§		1.4		1.7		1.4	

§ This information was not available at the time of publication.



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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	A	Y	†		1	4.2	4.2		1	3.6	ns
	LE		†		1.3	5	4.9		1.3	4.2	
	CLK		†		1.4	5.5	5.2		1.4	4.5	
t _{en}	OE	Y	†		1.4	5.5	5.6		1.1	4.6	ns
t _{dis}	OE	Y	†		1	4.5	4.3		1.3	3.9	ns

† This information was not available at the time of publication.

switching characteristics from 0°C to 65°C, C_L = 50 pF

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 3.3 V ± 0.15 V		UNIT
			MIN	MAX	
t _{pd}	CLK	Y	1.7	4.5	ns

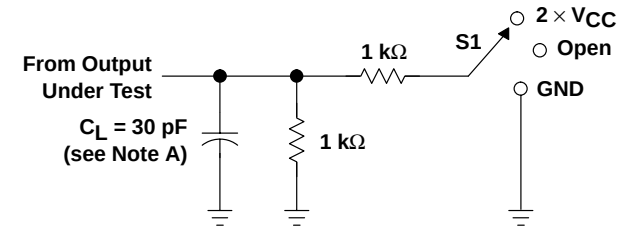
operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 50 pF, f = 10 MHz	†	26	31	pF
		Outputs disabled		†	12	14	

† This information was not available at the time of publication.

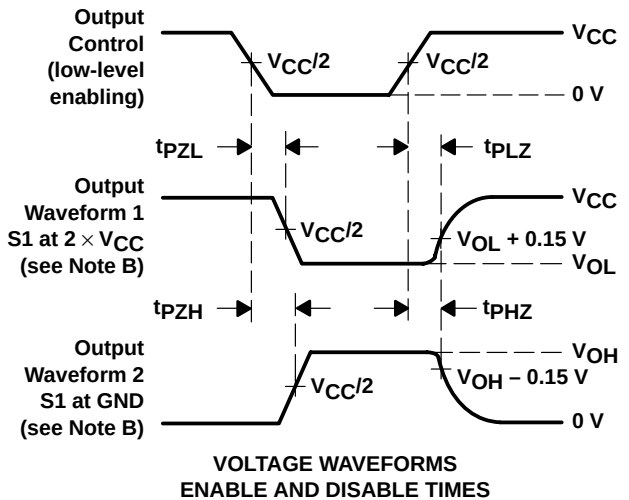
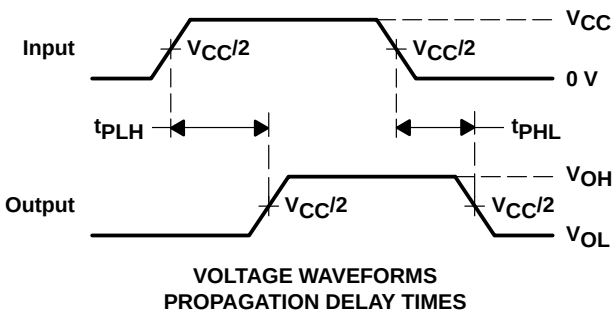
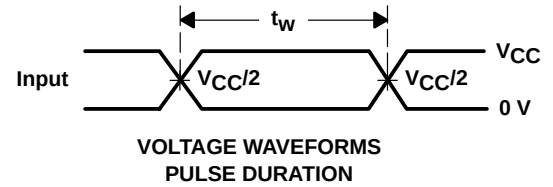
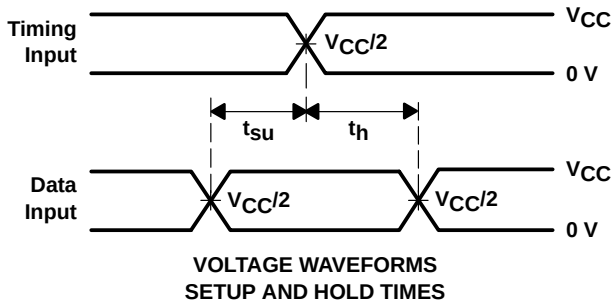


PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH16835

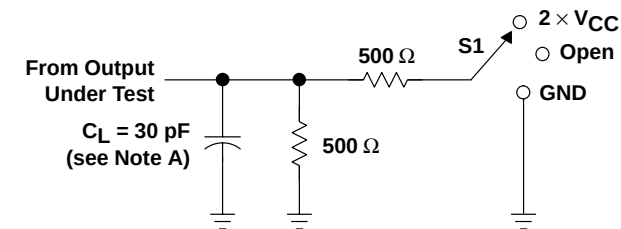
18-BIT UNIVERSAL BUS DRIVER

WITH 3-STATE OUTPUTS

SCES053E – SEPTEMBER 1995 – REVISED FEBRUARY 1999

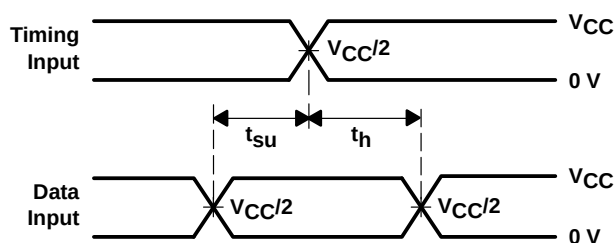
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

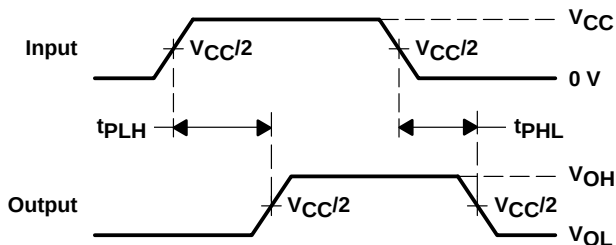


LOAD CIRCUIT

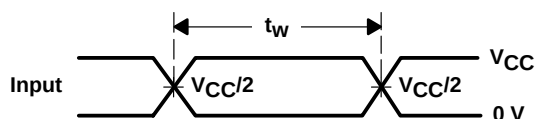
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



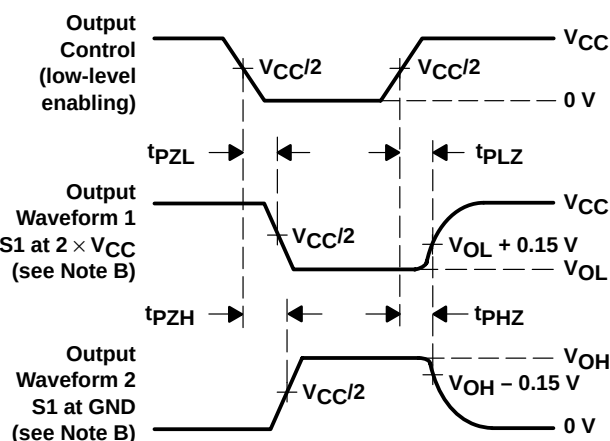
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



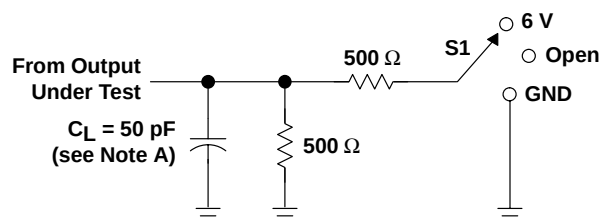
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

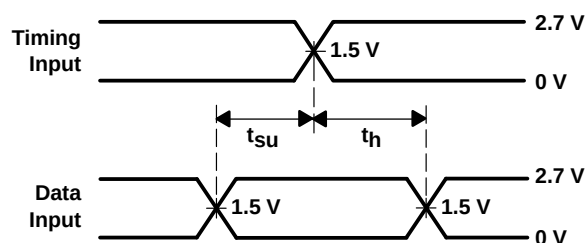
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

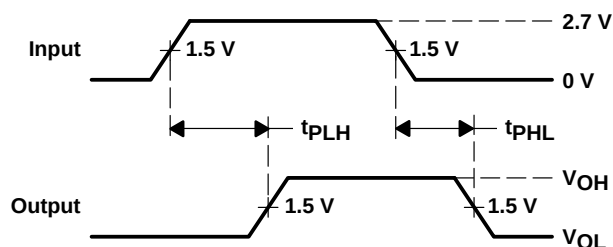


LOAD CIRCUIT

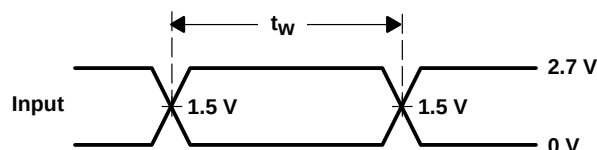
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



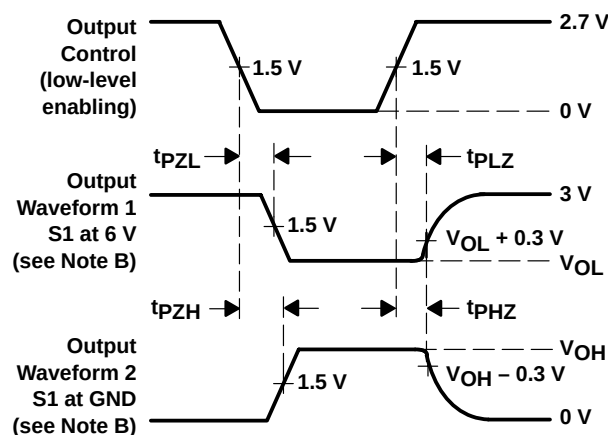
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16836 20-BIT UNIVERSAL BUS DRIVER WITH 3-STATE OUTPUTS

SCES089C – OCTOBER 1996 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- Designed to Comply With JEDEC 168-Pin and 200-Pin SDRAM Buffered DIMM Specification
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 20-bit universal bus driver is designed for 1.65-V to 3.6-V V_{CC} operation.

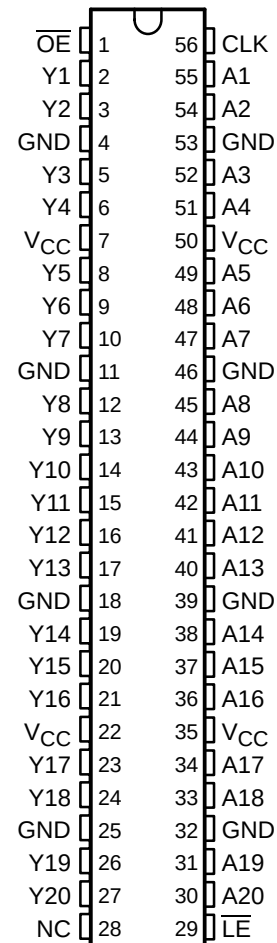
Data flow from A to Y is controlled by the output-enable ($\overline{OE}$) input. The device operates in the transparent mode when the latch-enable ($\overline{LE}$) input is low. The A data is latched if the clock ($\overline{CLK}$) input is held at a high or low logic level. If $\overline{LE}$ is high, the A data is stored in the latch/flip-flop on the low-to-high transition of $\overline{CLK}$. When $\overline{OE}$ is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16836 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)



NC – No internal connection

PRODUCT PREVIEW

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SN74ALVCH16836
20-BIT UNIVERSAL BUS DRIVER
WITH 3-STATE OUTPUTS

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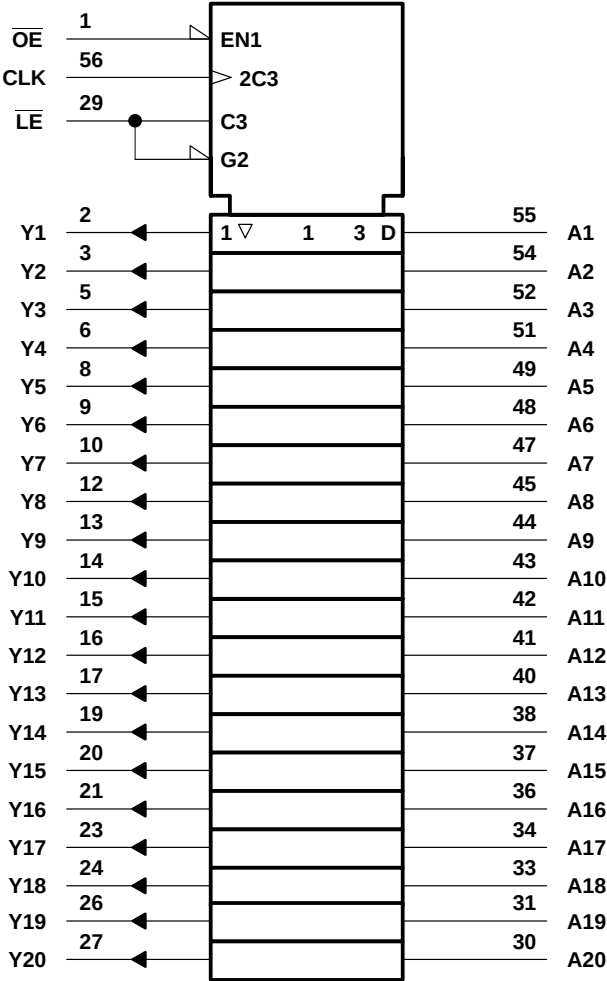
FUNCTION TABLE

INPUTS				OUTPUT Y
OE	LE	CLK	A	
H	X	X	X	Z
L	L	X	L	L
L	L	X	H	H
L	H	↑	L	L
L	H	↑	H	H
L	H	H	X	Y ₀ [†]
L	H	L	X	Y ₀ [‡]

† Output level before the indicated steady-state input conditions were established, provided that CLK is high before LE goes low

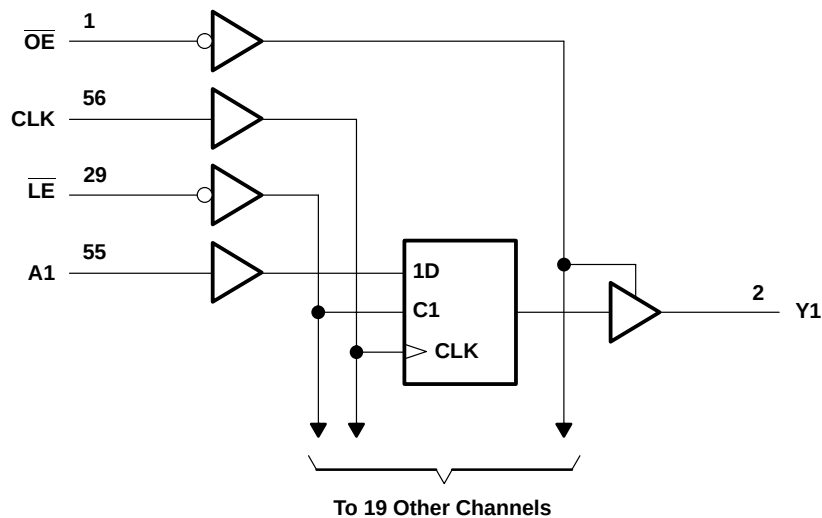
‡ Output level before the indicated steady-state input conditions were established

logic symbols



§ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{Stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

PRODUCT PREVIEW

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WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–4	mA
		$V_{CC} = 2.3 \text{ V}$	–12	
		$V_{CC} = 2.7 \text{ V}$	–12	
		$V_{CC} = 3 \text{ V}$	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	4	mA
		$V_{CC} = 2.3 \text{ V}$	12	
		$V_{CC} = 2.7 \text{ V}$	12	
		$V_{CC} = 3 \text{ V}$	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
		I _{OL} = 12 mA	2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V				pF
	Data inputs						
C _O	Outputs	V _O = V _{CC} or GND	3.3 V				pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

PRODUCT PREVIEW



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20-BIT UNIVERSAL BUS DRIVER
WITH 3-STATE OUTPUTS

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timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figures 1 through 3)

			V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency										MHz
t _w	Pulse duration	$\overline{LE}$ low									ns
		CLK high or low									
t _{su}	Setup time	Data before CLK↑									ns
		Data before $\overline{LE}$ ↑	CLK high								
			CLK low								
t _h	Hold time	Data after CLK↑									ns
		Data after $\overline{LE}$ ↑	CLK high or low								

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}											MHz
t _{pd}	A	Y									ns
	$\overline{LE}$										
	CLK										
t _{en}	$\overline{OE}$	Y									ns
t _{dis}	$\overline{OE}$	Y									ns

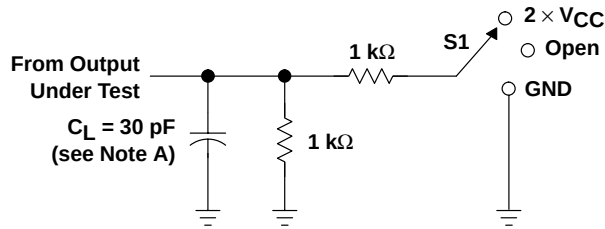
operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 0, f = 10 MHz				pF
		Outputs disabled					

PRODUCT PREVIEW

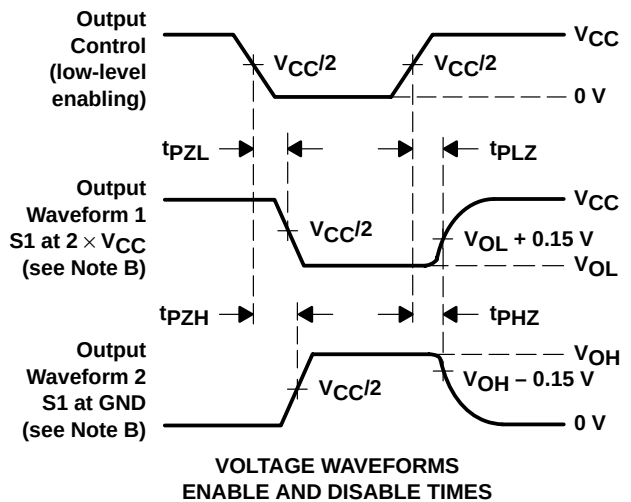
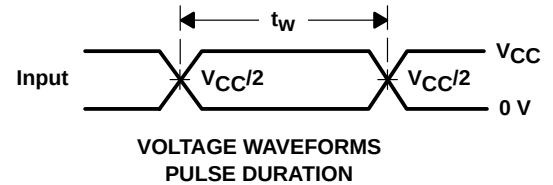
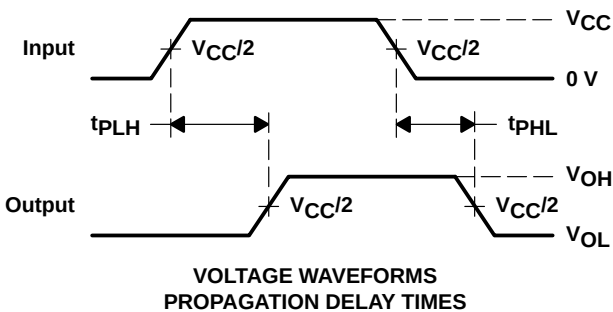
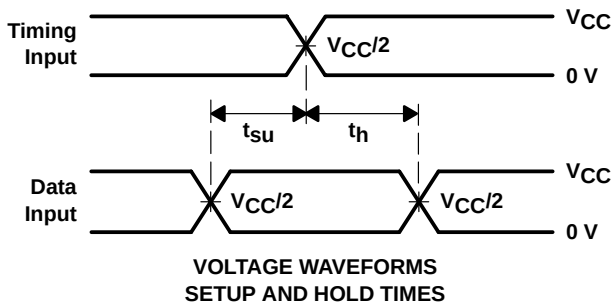


PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: PRR $\leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

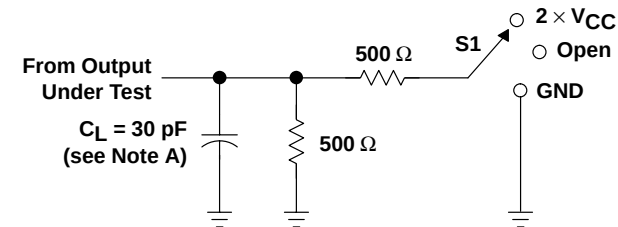
Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH16836 20-BIT UNIVERSAL BUS DRIVER WITH 3-STATE OUTPUTS

SCES089C – OCTOBER 1996 – REVISED FEBRUARY 1999

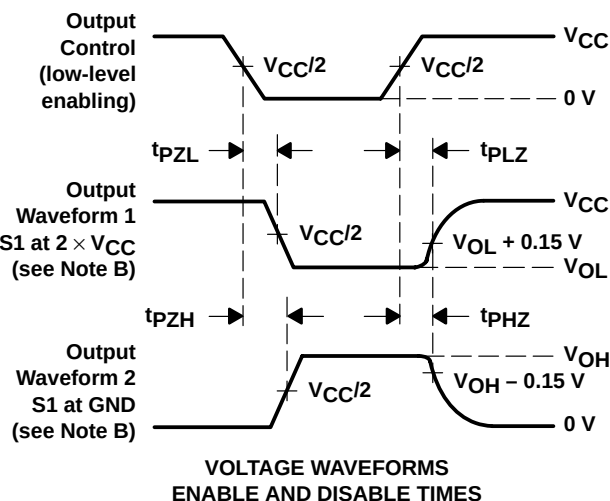
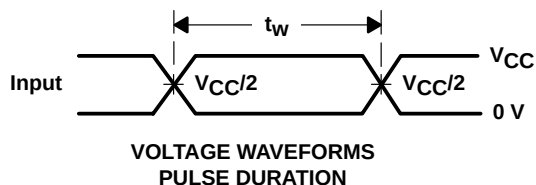
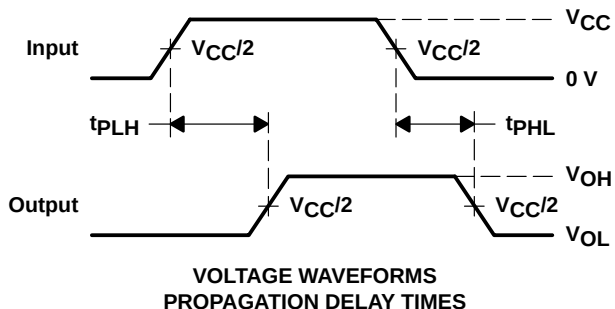
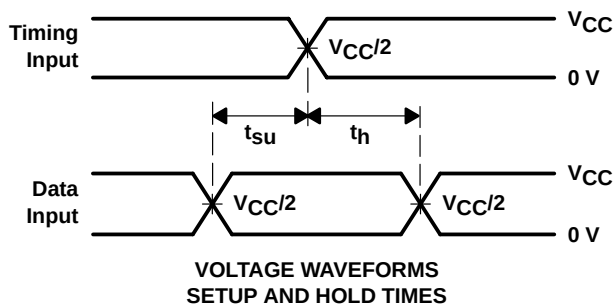
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND

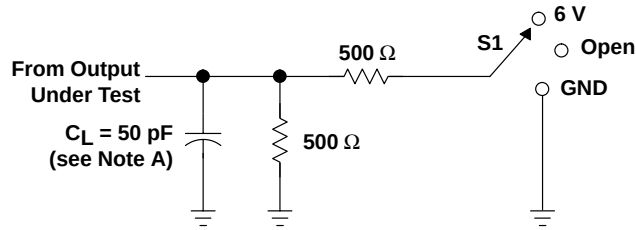


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

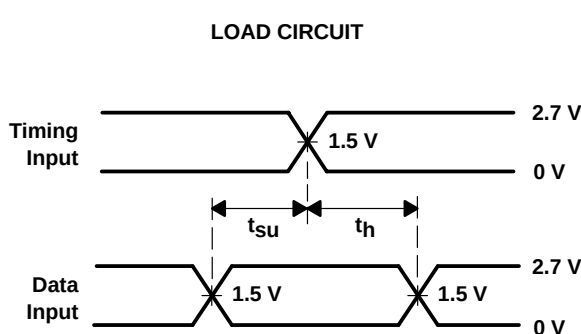
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

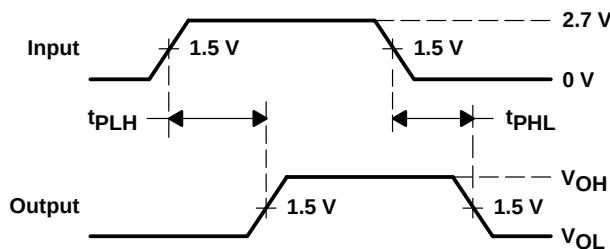


LOAD CIRCUIT

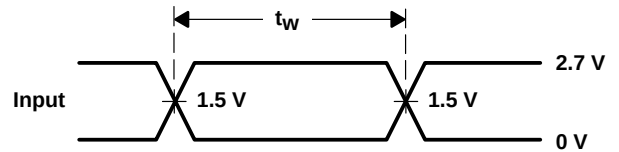
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



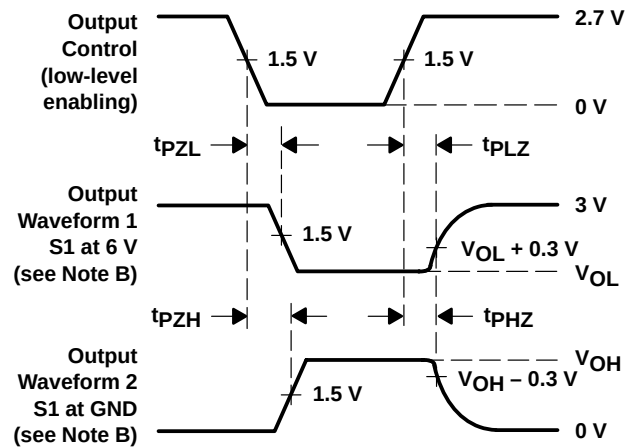
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16841

20-BIT BUS-INTERFACE D-TYPE LATCH WITH 3-STATE OUTPUTS

SCES043D – JULY 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 20-bit bus-interface D-type latch is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16841 features 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. This device is particularly suitable for implementing buffer registers, unidirectional bus drivers, and working registers.

The SN74ALVCH16841 can be used as two 10-bit latches or one 20-bit latch. The 20 latches are transparent D-type latches. The device has noninverting data (D) inputs and provides true data at its outputs. While the latch-enable (1LE or 2LE) input is high, the Q outputs of the corresponding 10-bit latch follow the D inputs. When LE is taken low, the Q outputs are latched at the levels set up at the D inputs.

A buffered output-enable ($\overline{1OE}$ or $\overline{2OE}$) input can be used to place the outputs of the corresponding 10-bit latch in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly.

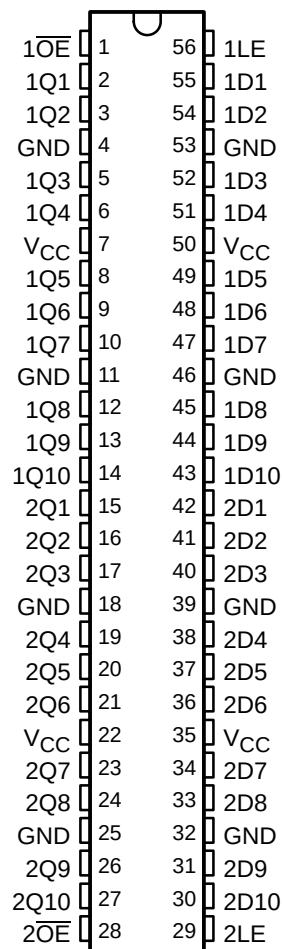
$\overline{OE}$ does not affect the internal operation of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16841 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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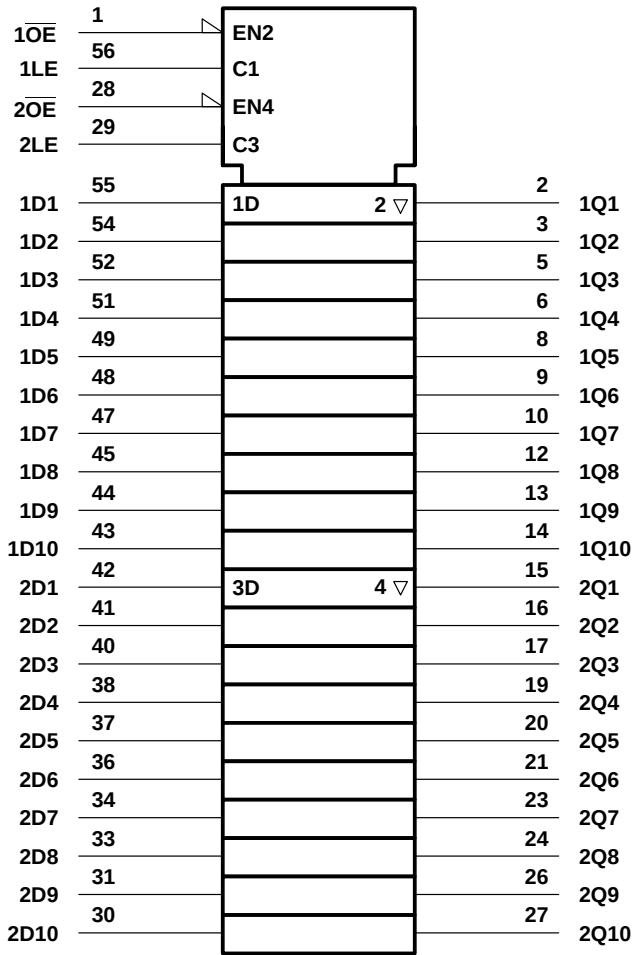
SN74ALVCH16841
20-BIT BUS-INTERFACE D-TYPE LATCH
WITH 3-STATE OUTPUTS

SCES043D – JULY 1995 – REVISED FEBRUARY 1999

FUNCTION TABLE
(each 10-bit latch)

INPUTS			OUTPUT Q
OE	LE	D	
L	H	H	H
L	H	L	L
L	L	X	Q ₀
H	X	X	Z

logic symbol†

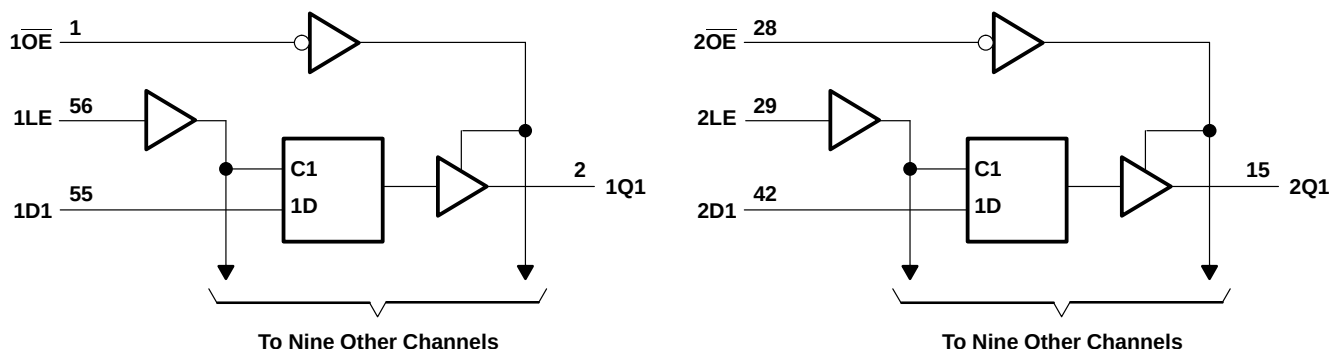


† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

SN74ALVCH16841
20-BIT BUS-INTERFACE D-TYPE LATCH
WITH 3-STATE OUTPUTS

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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

SN74ALVCH16841

20-BIT BUS-INTERFACE D-TYPE LATCH

WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–4	mA
		$V_{CC} = 2.3 \text{ V}$	–12	
		$V_{CC} = 2.7 \text{ V}$	–12	
		$V_{CC} = 3 \text{ V}$	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	4	mA
		$V_{CC} = 2.3 \text{ V}$	12	
		$V_{CC} = 2.7 \text{ V}$	12	
		$V_{CC} = 3 \text{ V}$	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

SN74ALVCH16841
20-BIT BUS-INTERFACE D-TYPE LATCH
WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V			±5	µA
I _{I(hold)}	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V			±500	
I _{OZ}	V _O = V _{CC} or GND	3.6 V			±10	µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V			40	µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V			750	µA
C _i	Control inputs	3.3 V			4.5	pF
	Data inputs				6.5	
C _O	Outputs	3.3 V			7	pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t _w	Pulse duration, LE high or low	§		3.3		3.3		3.3		ns
t _{su}	Setup time, data before LE↑	§		0.9		0.7		1.1		ns
t _h	Hold time, data after LE↑	§		1.2		1.5		1.1		ns

§ This information was not available at time of publication.



SN74ALVCH16841
20-BIT BUS-INTERFACE D-TYPE LATCH
WITH 3-STATE OUTPUTS

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	D	Q	†	1	5	4.7		1.2	3.9	ns
	LE		†	1	5.6	5.1		1	4.3	
t _{en}	$\overline{OE}$	Q	†	1	6.2	6		1	4.9	ns
t _{dis}	$\overline{OE}$	Q	†	1.1	5.3	4.3		1.3	4.1	ns

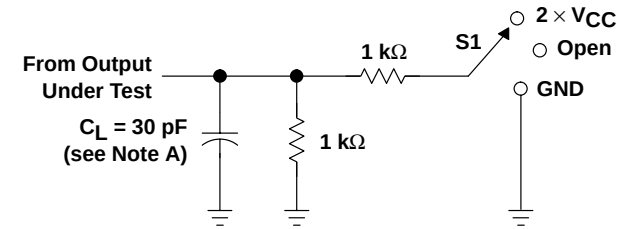
† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd} Power dissipation capacitance	Outputs enabled	C _L = 50 pF, f = 10 MHz	†		12	20	pF
	Outputs disabled		†		1	3	

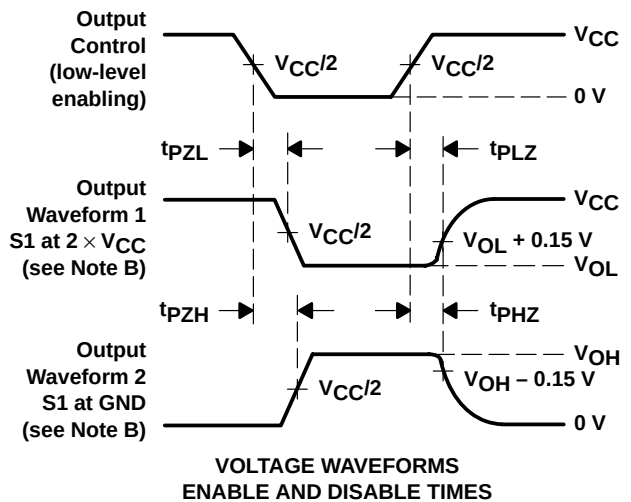
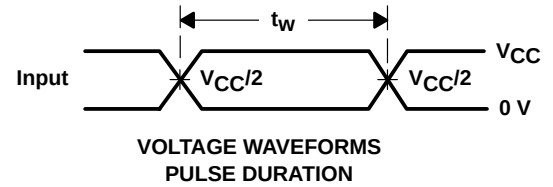
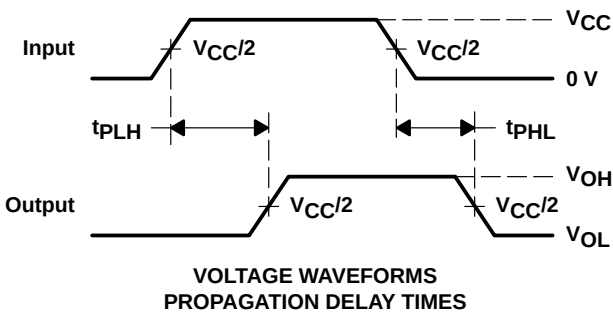
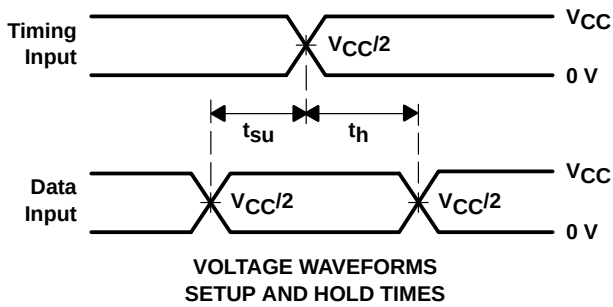
† This information was not available at the time of publication.

PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH16841

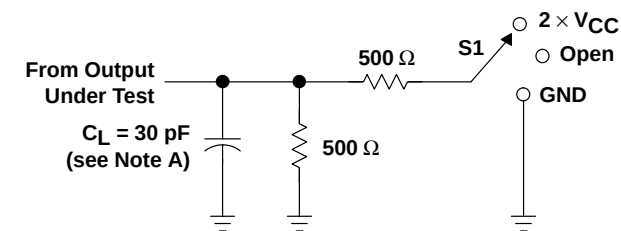
20-BIT BUS-INTERFACE D-TYPE LATCH

WITH 3-STATE OUTPUTS

SCES043D – JULY 1995 – REVISED FEBRUARY 1999

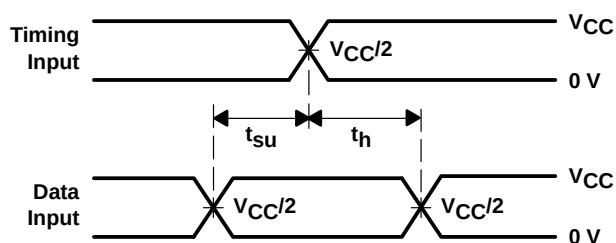
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

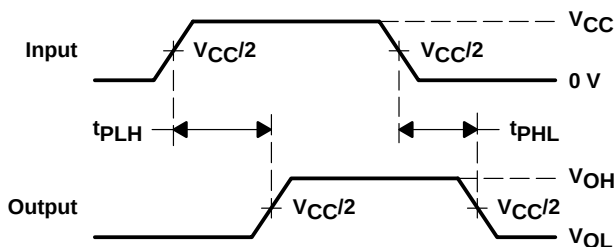


LOAD CIRCUIT

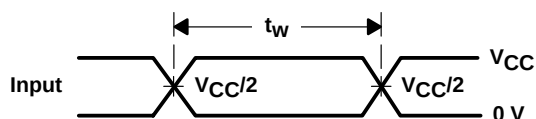
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



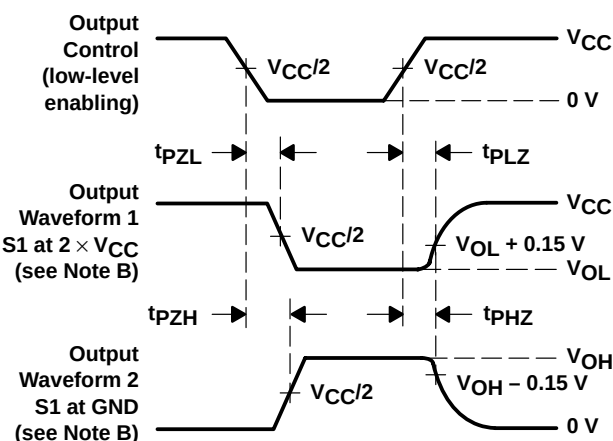
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



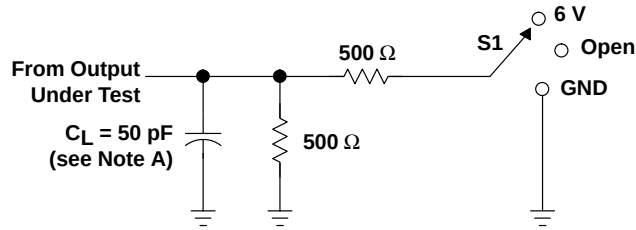
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

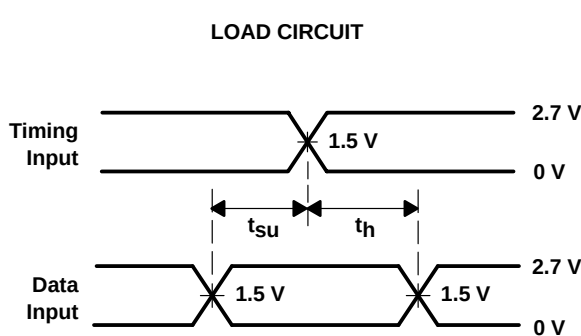
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

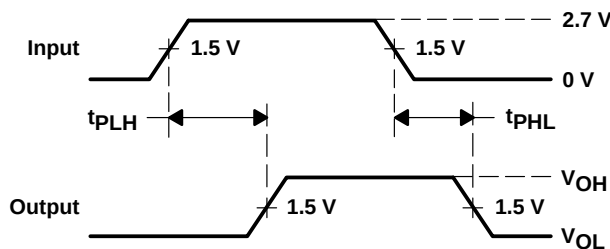


LOAD CIRCUIT

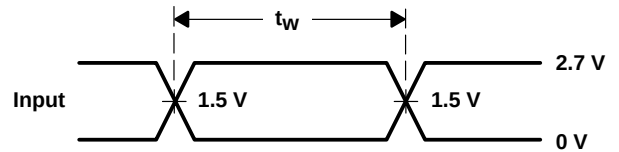
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



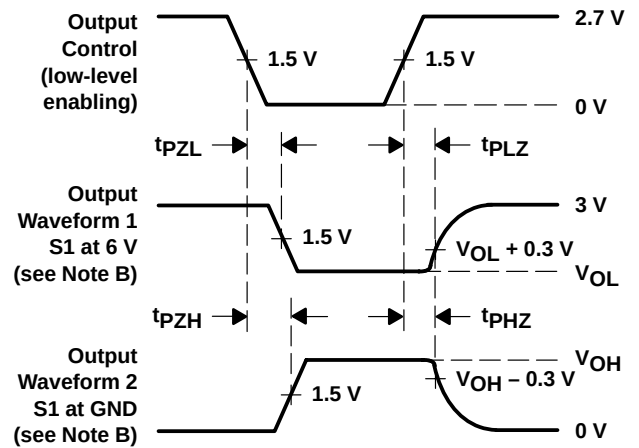
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16843

18-BIT BUS-INTERFACE D-TYPE LATCH

WITH 3-STATE OUTPUTS

SCES044C – JULY 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 18-bit bus-interface D-type latch is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16843 features 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. This device is particularly suitable for implementing buffer registers, unidirectional bus drivers, and working registers.

This device can be used as two 9-bit latches or one 18-bit latch. The 18 latches are transparent D-type latches. The device has noninverting data (D) inputs and provides true data at its outputs.

A buffered output-enable ($\overline{OE}$) input can be used to place the nine outputs in either a normal logic state (high or low logic levels) or the high-impedance state. The outputs also are in the high-impedance state during power-up and power-down conditions. The outputs remain in the high-impedance state while the device is powered down. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without need for interface or pullup components.

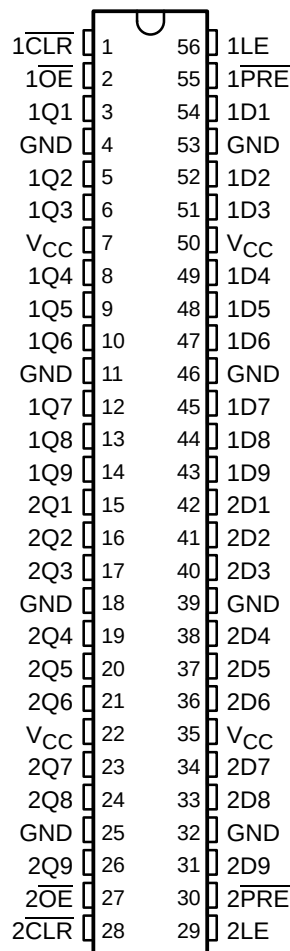
The output-enable ($\overline{OE}$) input does not affect the internal operations of the latch. Previously stored data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating inputs at a valid logic level.

The SN74ALVCH16843 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)



PRODUCT PREVIEW

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PRODUCT PREVIEW information concerns products in the formative or design phase of development. Characteristic data and other specifications are design goals. Texas Instruments reserves the right to change or discontinue these products without notice.



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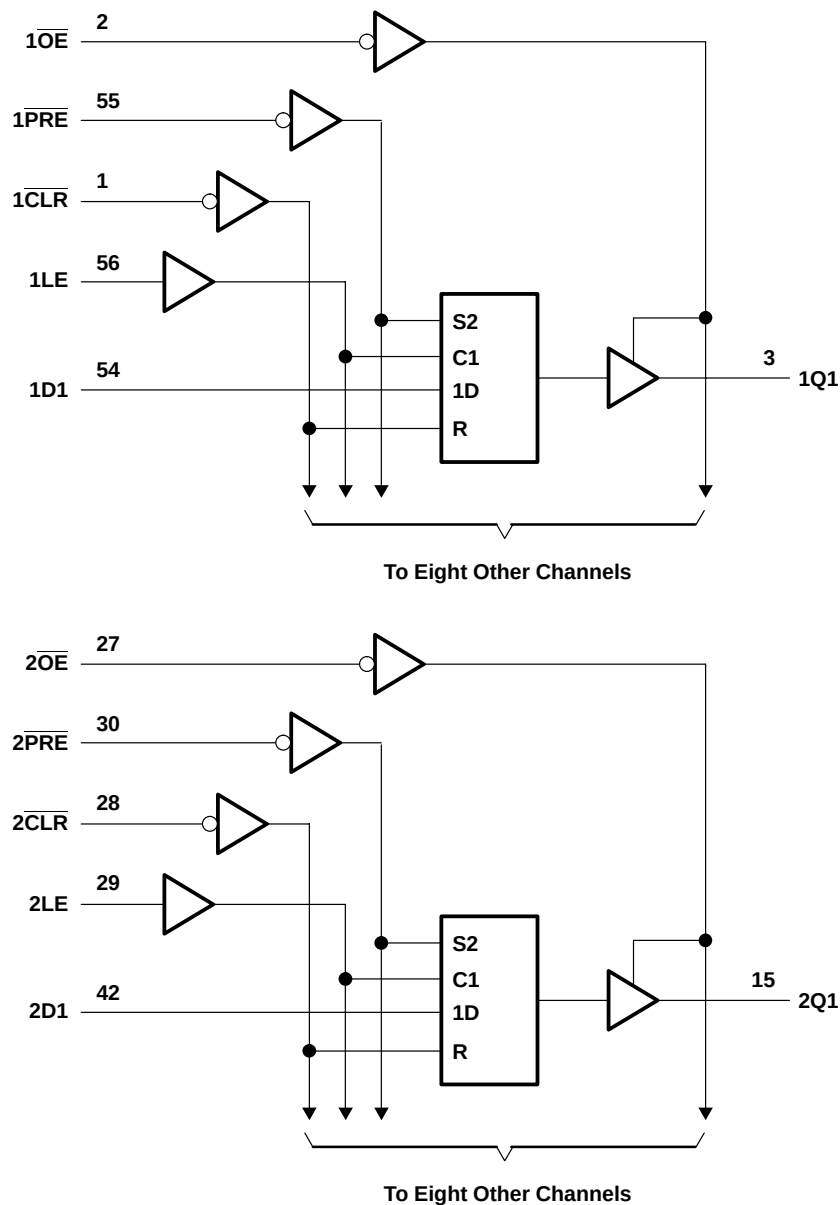
SN74ALVCH16843 18-BIT BUS-INTERFACE D-TYPE LATCH WITH 3-STATE OUTPUTS

SCES044C – JULY 1995 – REVISED FEBRUARY 1999

FUNCTION TABLE
(each 9-bit latch)

INPUTS					OUTPUT Q
PRE	CLR	OE	LE	D	
L	X	L	X	X	H
H	L	L	X	X	L
H	H	L	H	L	L
H	H	L	H	H	H
H	H	L	L	X	Q ₀
X	X	H	X	X	Z

logic diagram (positive logic)



SN74ALVCH16843
18-BIT BUS-INTERFACE D-TYPE LATCH
WITH 3-STATE OUTPUTS

SCES044C – JULY 1995 – REVISED FEBRUARY 1999

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate			10	ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

PRODUCT PREVIEW



SN74ALVCH16843
18-BIT BUS-INTERFACE D-TYPE LATCH
WITH 3-STATE OUTPUTS

SCES044C – JULY 1995 – REVISED FEBRUARY 1999

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 μA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA		2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 μA	1.65 V to 3.6 V			0.2	V
		I _{OL} = 4 mA	1.65 V			0.45	
		I _{OL} = 6 mA	2.3 V			0.4	
	I _{OL} = 12 mA		2.3 V			0.7	
			2.7 V			0.4	
		I _{OL} = 24 mA	3 V			0.55	
I _I	V _I = V _{CC} or GND		3.6 V			±5	μA
I _I (hold)		V _I = 0.58 V	1.65 V	25			μA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V			±500	
	I _{OZ}	V _O = V _{CC} or GND		3.6 V			
I _{CC}	V _I = V _{CC} or GND, I _O = 0		3.6 V			40	μA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND		3 V to 3.6 V		750	μA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V				pF
	Data inputs						
C _O	Outputs	V _O = V _{CC} or GND	3.3 V				pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t _w	Pulse duration	$\overline{\text{PRE}}$ or $\overline{\text{CLR}}$ low									ns
		LE high or low									
t _{su}	Setup time	Data high before LE↓									ns
		Data low before LE↓									
		$\overline{\text{PRE}}$ inactive before LE↓									
		$\overline{\text{CLR}}$ inactive before LE↓									
t _h	Hold time	Data after LE↓									ns



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WITH 3-STATE OUTPUTS

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	D	Q								ns
	LE									
	PRE or CLR									
t _{en}	OE	Q								ns
t _{dis}	OE	Q								ns

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 0, f = 10 MHz				pF
		Outputs disabled					

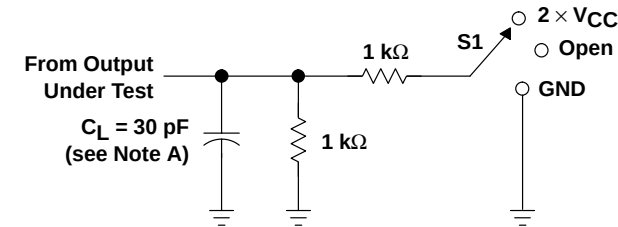
PRODUCT PREVIEW



SN74ALVCH16843
18-BIT BUS-INTERFACE D-TYPE LATCH
WITH 3-STATE OUTPUTS

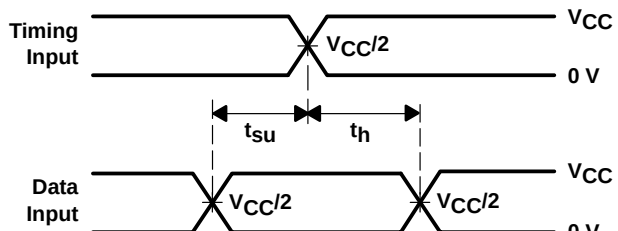
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PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8\text{ V}$

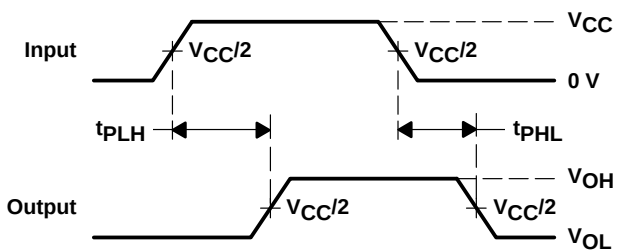


LOAD CIRCUIT

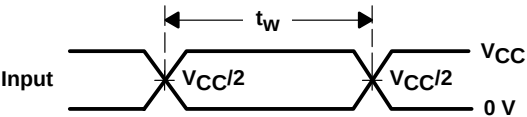
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PHL}	GND



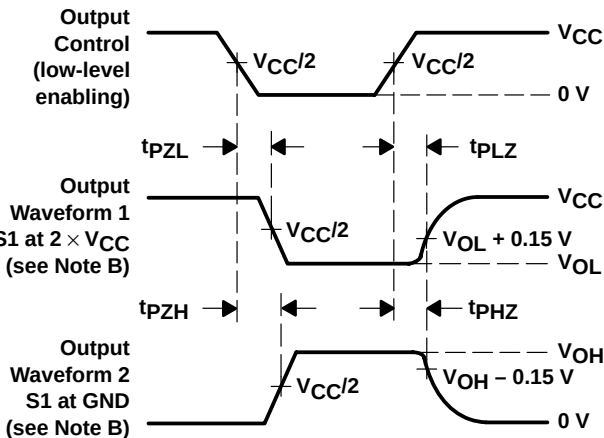
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



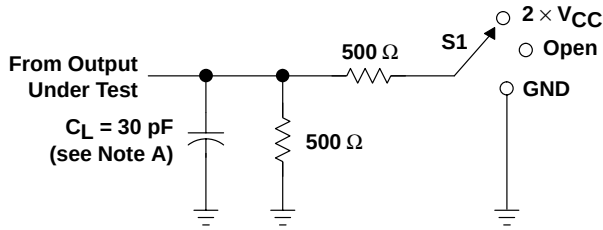
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

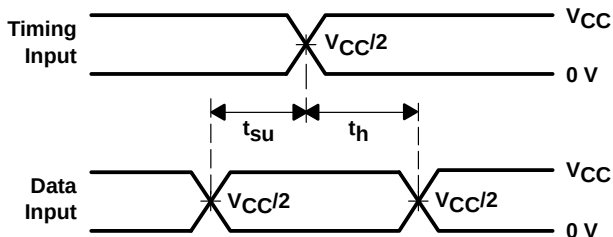
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

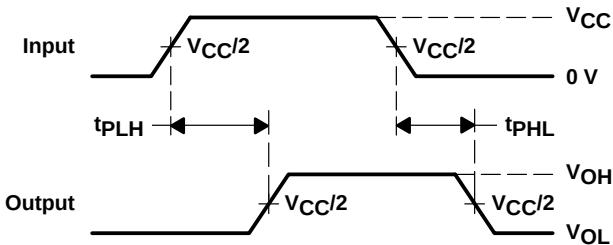


LOAD CIRCUIT

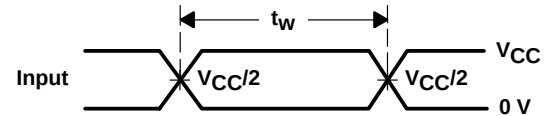
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times$ V_{CC}
t_{PHZ}/t_{PZH}	GND



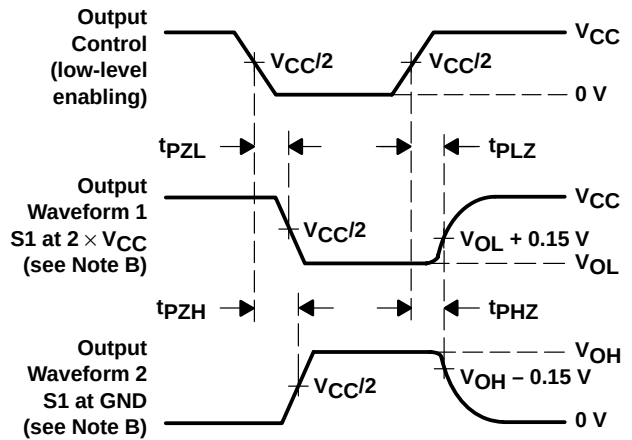
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

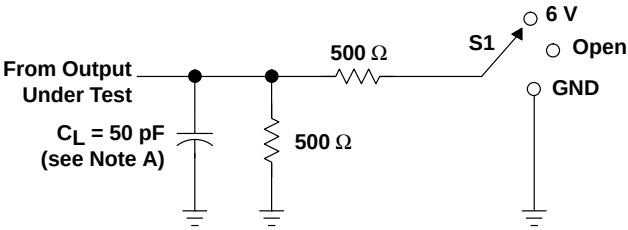
- NOTES: A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
- D. The outputs are measured one at a time with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH16843
18-BIT BUS-INTERFACE D-TYPE LATCH
WITH 3-STATE OUTPUTS

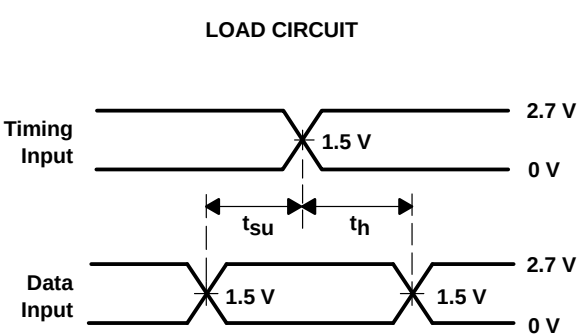
SCES044C – JULY 1995 – REVISED FEBRUARY 1999

PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

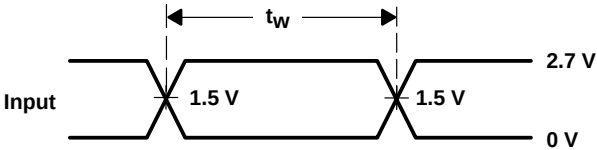


LOAD CIRCUIT

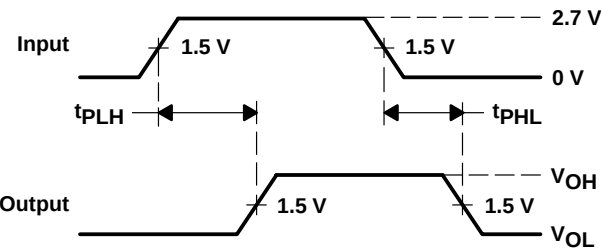
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



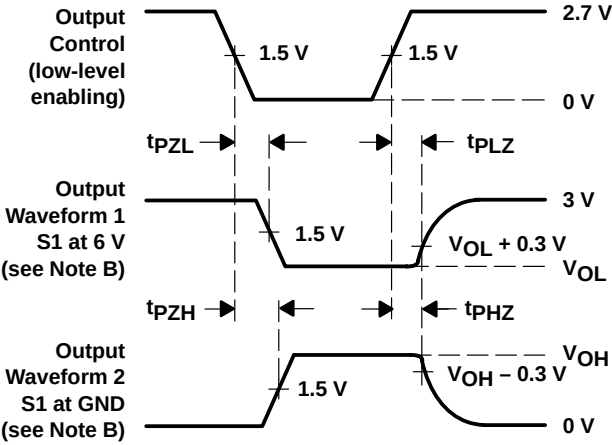
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
D. The outputs are measured one at a time with one transition per measurement.
E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
F. t_{PZL} and t_{PZH} are the same as t_{en} .
G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16863 18-BIT TRANSCEIVER WITH 3-STATE OUTPUTS

SCES060B – DECEMBER 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 18-bit bus transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16863 is an 18-bit noninverting transceiver designed for synchronous communication between data buses. The control-function implementation minimizes external timing requirements.

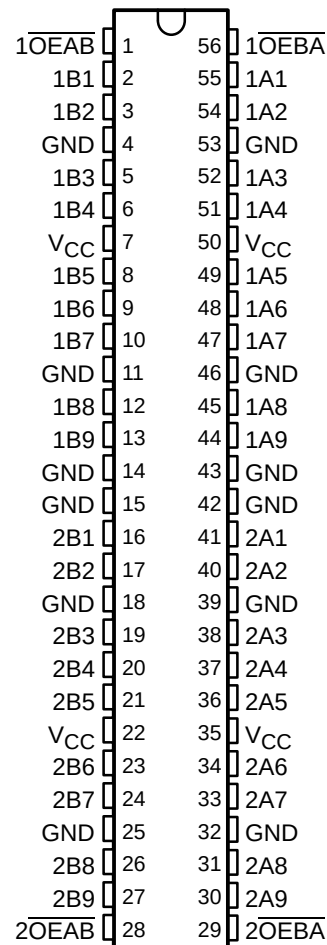
The SN74ALVCH16863 can be used as two 9-bit transceivers or one 18-bit transceiver. They allow data transmission from the A bus to the B bus or from the B bus to the A bus, depending on the logic level at the output-enable ($\overline{OEAB}$ or $\overline{OEBA}$) inputs.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16863 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)



FUNCTION TABLE
(each 9-bit section)

INPUTS		OPERATION
$\overline{OEAB}$	$\overline{OEBA}$	
H	L	B data to A bus
L	H	A data to B bus
H	H	Isolation

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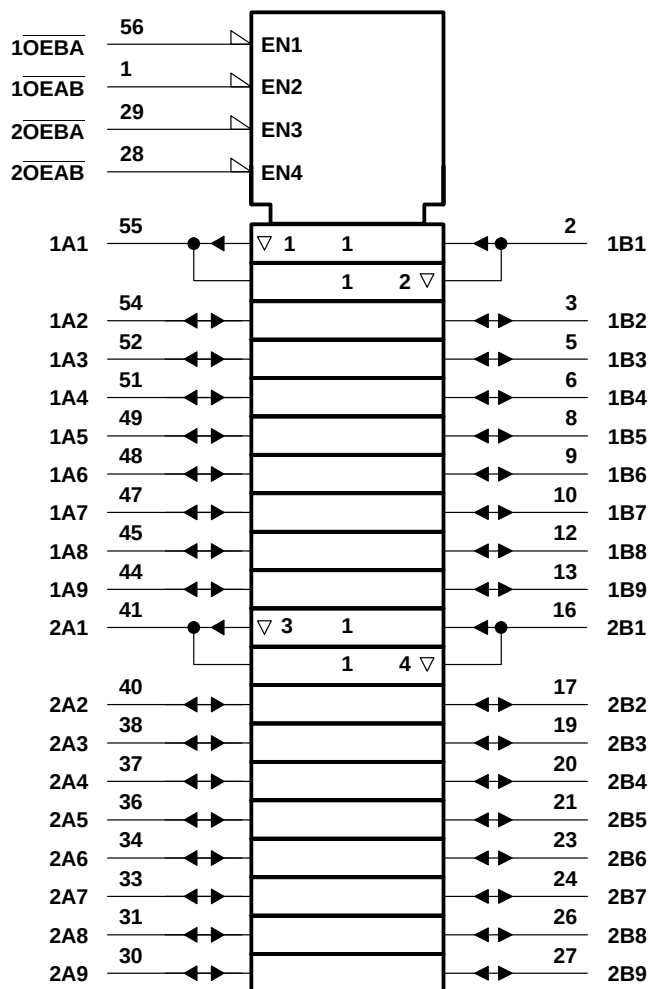
SN74ALVCH16863

18-BIT TRANSCEIVER

WITH 3-STATE OUTPUTS

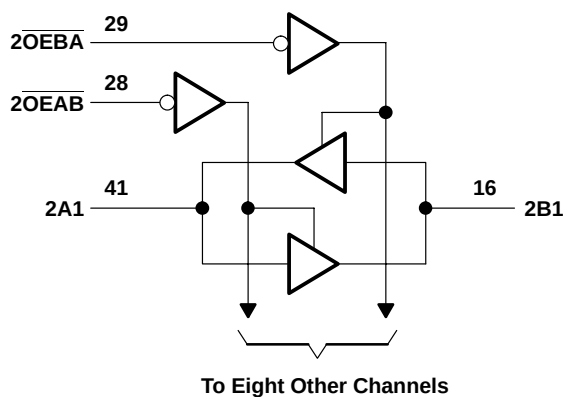
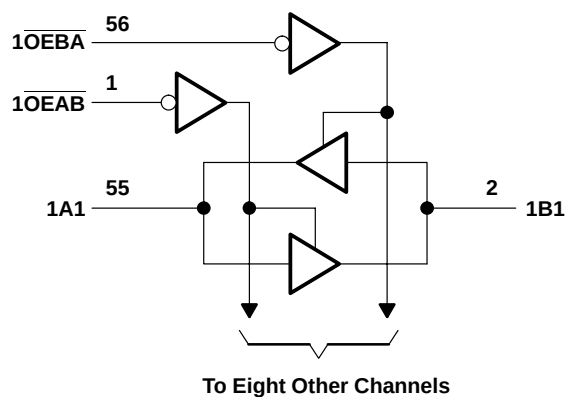
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logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–4	mA
		$V_{CC} = 2.3$ V	–12	
		$V_{CC} = 2.7$ V	–12	
		$V_{CC} = 3$ V	–24	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	4	mA
		$V_{CC} = 2.3$ V	12	
		$V_{CC} = 2.7$ V	12	
		$V_{CC} = 3$ V	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

SN74ALVCH16863
18-BIT TRANSCEIVER
WITH 3-STATE OUTPUTS

SCES060B – DECEMBER 1995 – REVISED FEBRUARY 1999

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	3.3 V	3.5			pF
	Data inputs		6			
C _O	Outputs	3.3 V	7.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A or B	B or A	§	1	4.1	4		1	3.4	ns
t _{en}	OEAB or OEBA	A or B	§	1	5.7	5.8		1	4.7	ns
t _{dis}	OEAB or OEBA	A or B	§	1.3	5.5	4.7		1.4	4.2	ns

§ This information was not available at the time of publication.

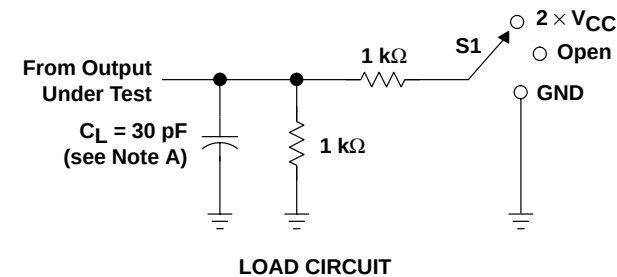


operating characteristics, $T_A = 25^\circ\text{C}$

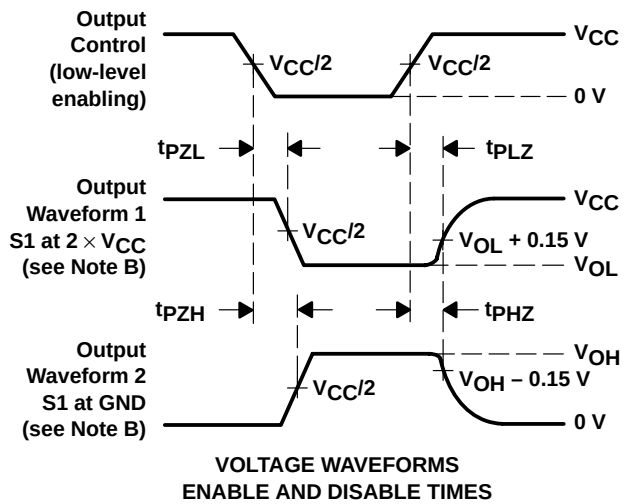
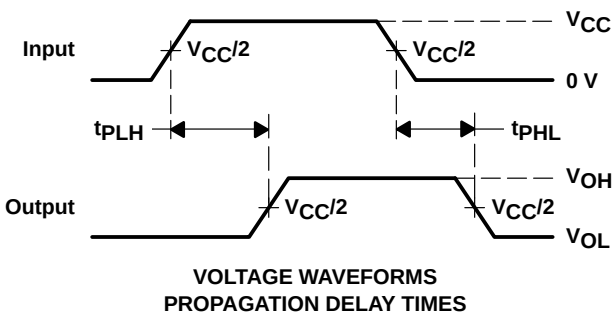
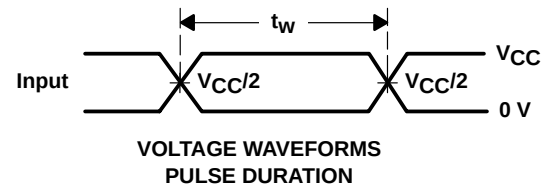
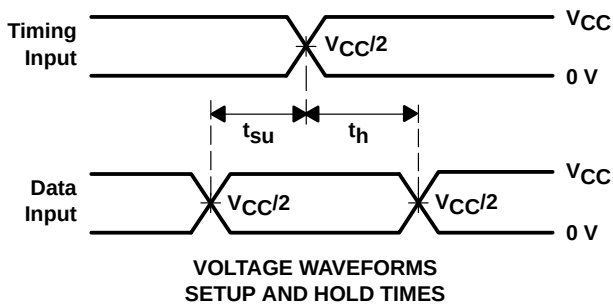
PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd} Power dissipation capacitance	Outputs enabled	$C_L = 50\text{ pF}$, $f = 10\text{ MHz}$	†	21	30	pF
	Outputs disabled		†	2	3	

† This information was not available at the time of publication.

PARAMETER MEASUREMENT INFORMATION $V_{CC} = 1.8\text{ V}$



TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH16863

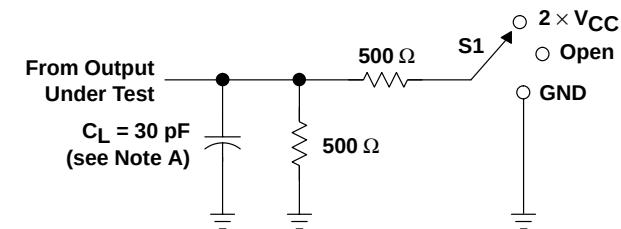
18-BIT TRANSCEIVER

WITH 3-STATE OUTPUTS

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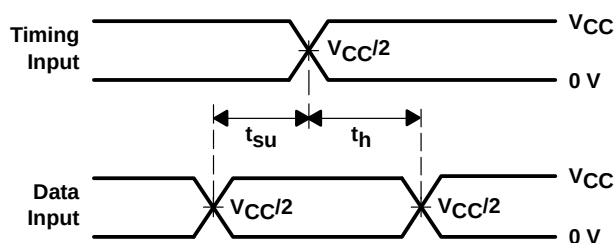
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

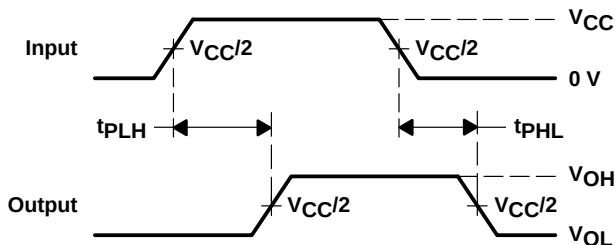


LOAD CIRCUIT

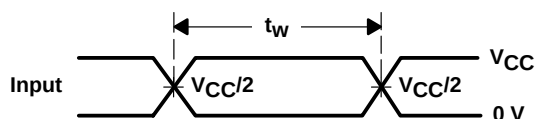
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



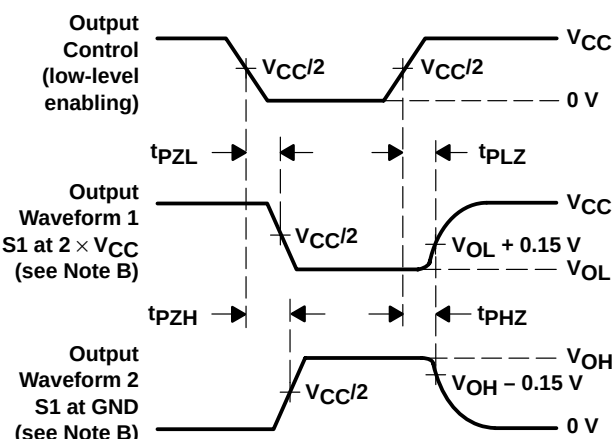
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



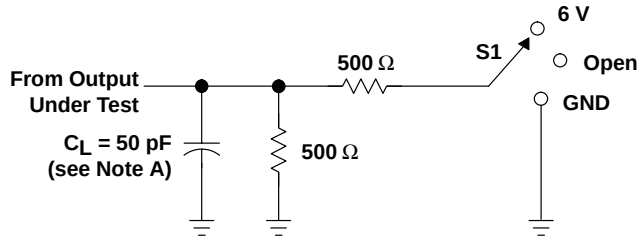
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

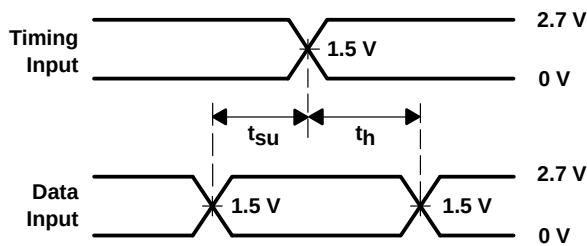
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

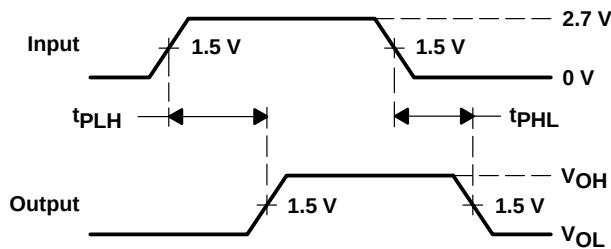


LOAD CIRCUIT

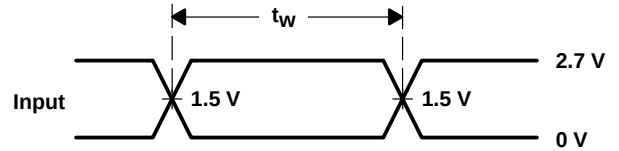
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



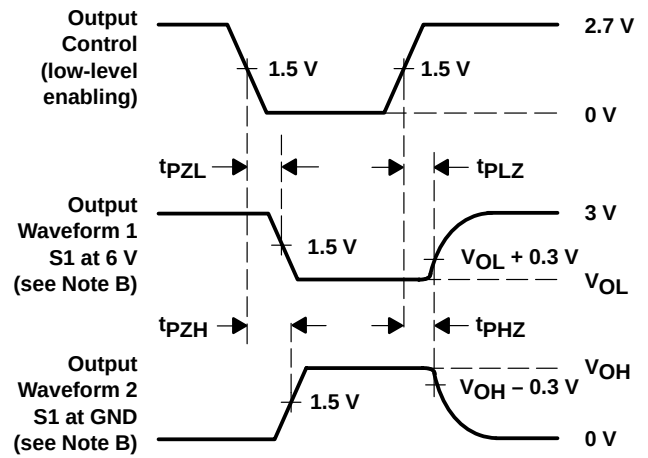
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
D. The outputs are measured one at a time with one transition per measurement.
E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
F. t_{PZL} and t_{PZH} are the same as t_{en} .
G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16901

18-BIT UNIVERSAL BUS TRANSCEIVER WITH PARITY GENERATORS/CHECKERS

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- Member of the Texas Instruments *Widebus+*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- *UBT*™ (Universal Bus Transceiver) Combines D-Type Latches and D-Type Flip-Flops for Operation in Transparent, Latched, or Clocked Mode
- Simultaneously Generates and Checks Parity
- Option to Select Generate Parity and Check or Feed-Through Data/Parity in A-to-B or B-to-A Directions
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Packaged in Thin Shrink Small-Outline Package

description

This 18-bit (dual-octal) noninverting registered transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16901 is a dual 9-bit to dual 9-bit parity transceiver with registers. The device can operate as a feed-through transceiver or it can generate/check parity from the two 8-bit data buses in either direction.

The SN74ALVCH16901 features independent clock (CLKAB or CLKBA), latch-enable ($\overline{LEAB}$ or LEBA), and dual 9-bit clock-enable ($\overline{CLKENAB}$ or CLKENBA) inputs. It also provides parity-enable ($\overline{SEL}$) and parity-select (ODD/EVEN) inputs and separate error-signal ($\overline{ERRA}$ or $\overline{ERRB}$) outputs for checking parity. The direction of data flow is controlled by $\overline{OEAB}$ and OEBA. When $\overline{SEL}$ is low, the parity functions are enabled. When $\overline{SEL}$ is high, the parity functions are disabled and the device acts as an 18-bit registered transceiver.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16901 is characterized for operation from -40°C to 85°C .

DGG PACKAGE
(TOP VIEW)

$\overline{1CLKENAB}$	1	64	$\overline{1CLKENBA}$
$\overline{LEAB}$	2	63	LEBA
CLKAB	3	62	CLKBA
$\overline{1ERRA}$	4	61	$\overline{1ERRB}$
$\overline{1APAR}$	5	60	$\overline{1BPAR}$
GND	6	59	GND
$\overline{1A1}$	7	58	$\overline{1B1}$
$\overline{1A2}$	8	57	$\overline{1B2}$
$\overline{1A3}$	9	56	$\overline{1B3}$
V_{CC}	10	55	V_{CC}
$\overline{1A4}$	11	54	$\overline{1B4}$
$\overline{1A5}$	12	53	$\overline{1B5}$
$\overline{1A6}$	13	52	$\overline{1B6}$
GND	14	51	GND
$\overline{1A7}$	15	50	$\overline{1B7}$
$\overline{1A8}$	16	49	$\overline{1B8}$
$\overline{2A1}$	17	48	$\overline{2B1}$
$\overline{2A2}$	18	47	$\overline{2B2}$
GND	19	46	GND
$\overline{2A3}$	20	45	$\overline{2B3}$
$\overline{2A4}$	21	44	$\overline{2B4}$
$\overline{2A5}$	22	43	$\overline{2B5}$
V_{CC}	23	42	V_{CC}
$\overline{2A6}$	24	41	$\overline{2B6}$
$\overline{2A7}$	25	40	$\overline{2B7}$
$\overline{2A8}$	26	39	$\overline{2B8}$
GND	27	38	GND
$\overline{2APAR}$	28	37	$\overline{2BPAR}$
$\overline{2ERRA}$	29	36	$\overline{2ERRB}$
$\overline{OEAB}$	30	35	OEBA
$\overline{SEL}$	31	34	ODD/EVEN
$\overline{2CLKENAB}$	32	33	$\overline{2CLKENBA}$

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Function Tables

FUNCTION†					
INPUTS					OUTPUT B
CLKENAB	OEAB	LEAB	CLKAB	A	
X	H	X	X	X	Z
X	L	H	X	L	L
X	L	H	X	H	H
H	L	L	X	X	B ₀ ‡
L	L	L	↑	L	L
L	L	L	↑	H	H
L	L	L	L	X	B ₀ ‡
L	L	L	H	X	B ₀ §

† A-to-B data flow is shown: B-to-A flow is similar, but uses OEBA, LEBA, and CLKENBA.

‡ Output level before the indicated steady-state input conditions were established

§ Output level before the indicated steady-state input conditions were established, provided that CLKAB was low before LEAB went low

PARITY ENABLE

INPUTS			OPERATION OR FUNCTION
SEL	OEBA	OEAB	
L	H	L	Parity is checked on port A and is generated on port B.
L	L	H	Parity is checked on port B and is generated on port A.
L	H	H	Parity is checked on port B and port A.
L	L	L	Parity is generated on port A and B if device is in FF mode.
H	L	L	Parity functions are disabled; device acts as a standard 18-bit registered transceiver.
H	L	H	
H	H	L	
H	H	H	

Function Tables (Continued)

PARITY											
INPUTS								OUTPUTS			
SEL	OEBA	OEAB	ODD/EVEN	Σ OF INPUTS A1–A8 = H	Σ OF INPUTS B1–B8 = H	APAR	BPAR	APAR	$\overline{\text{ERRA}}$	BPAR	$\overline{\text{ERRB}}$
L	H	L	L	0, 2, 4, 6, 8	N/A	L	N/A	N/A	H	L	Z
L	H	L	L	1, 3, 5, 7	N/A	L	N/A	N/A	L	H	Z
L	H	L	L	0, 2, 4, 6, 8	N/A	H	N/A	N/A	L	L	Z
L	H	L	L	1, 3, 5, 7	N/A	H	N/A	N/A	H	H	Z
L	L	H	L	N/A	0, 2, 4, 6, 8	N/A	L	L	Z	N/A	H
L	L	H	L	N/A	1, 3, 5, 7	N/A	L	H	Z	N/A	L
L	L	H	L	N/A	0, 2, 4, 6, 8	N/A	H	L	Z	N/A	L
L	L	H	L	N/A	1, 3, 5, 7	N/A	H	H	Z	N/A	H
L	H	L	H	0, 2, 4, 6, 8	N/A	L	N/A	N/A	L	H	Z
L	H	L	H	1, 3, 5, 7	N/A	L	N/A	N/A	H	L	Z
L	H	L	H	0, 2, 4, 6, 8	N/A	H	N/A	N/A	H	H	Z
L	H	L	H	1, 3, 5, 7	N/A	H	N/A	N/A	L	L	Z
L	L	H	H	N/A	0, 2, 4, 6, 8	N/A	L	H	Z	N/A	L
L	L	H	H	N/A	1, 3, 5, 7	N/A	L	L	Z	N/A	H
L	L	H	H	N/A	0, 2, 4, 6, 8	N/A	H	H	Z	N/A	H
L	L	H	H	N/A	1, 3, 5, 7	N/A	H	H	L	Z	L
L	H	H	L	0, 2, 4, 6, 8	0, 2, 4, 6, 8	L	L	Z	H	Z	H
L	H	H	L	1, 3, 5, 7	1, 3, 5, 7	L	L	Z	L	Z	L
L	H	H	L	0, 2, 4, 6, 8	0, 2, 4, 6, 8	H	H	Z	L	Z	L
L	H	H	L	1, 3, 5, 7	1, 3, 5, 7	H	H	Z	H	Z	H
L	H	H	H	0, 2, 4, 6, 8	0, 2, 4, 6, 8	L	L	Z	L	Z	L
L	H	H	H	1, 3, 5, 7	1, 3, 5, 7	L	L	Z	H	Z	H
L	H	H	H	0, 2, 4, 6, 8	0, 2, 4, 6, 8	H	H	Z	H	Z	H
L	H	H	H	1, 3, 5, 7	1, 3, 5, 7	H	H	Z	L	Z	L
L	L	L	L	N/A	N/A	N/A	N/A	PE [†]	Z	PE [†]	Z
L	L	L	H	N/A	N/A	N/A	N/A	PO [‡]	Z	PO [‡]	Z

[†] Parity output is set to the level so that the specific bus side is set to even parity.

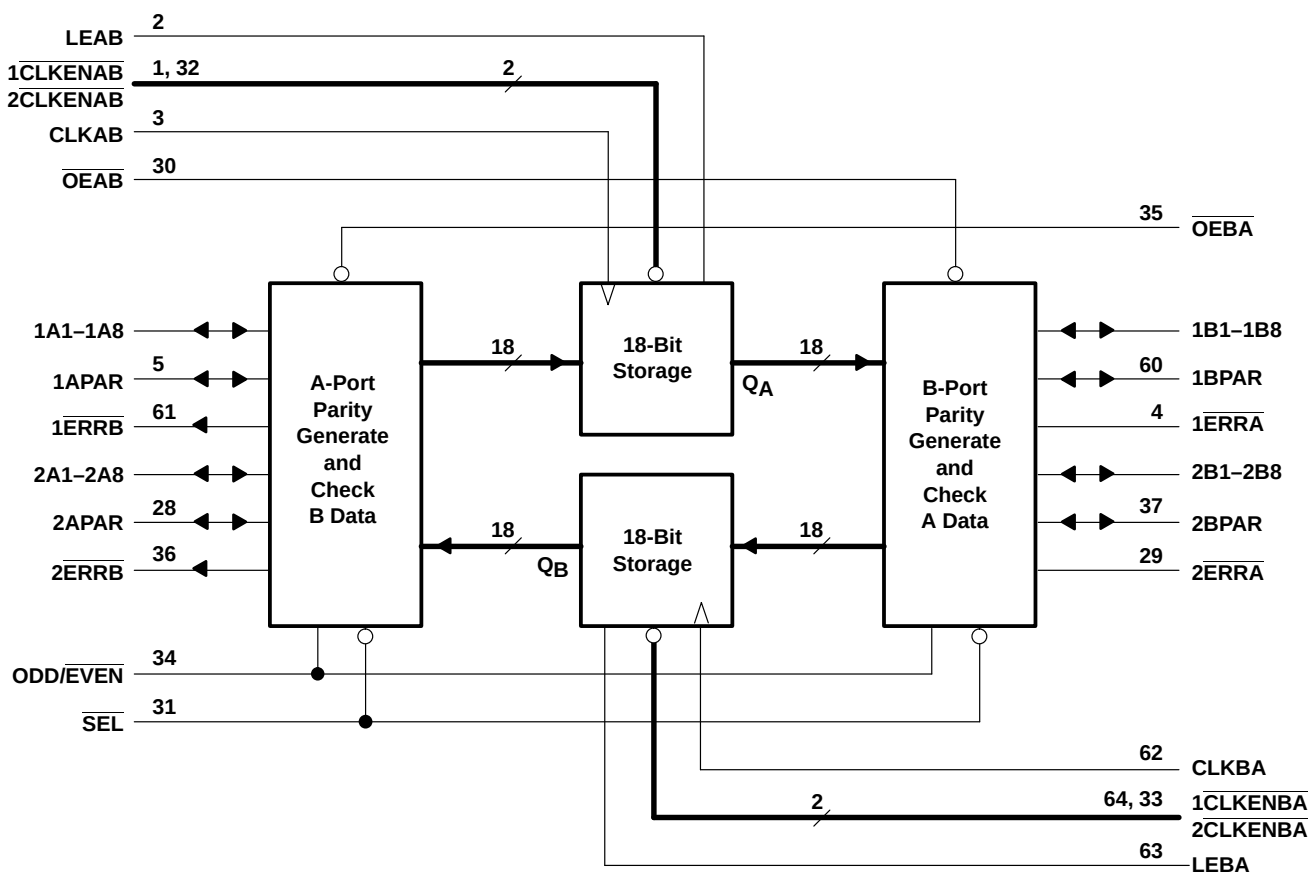
[‡] Parity output is set to the level so that the specific bus side is set to odd parity.

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functional block diagram



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3)	73°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.



recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate		10		ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} – 0.2			V
	I _{OH} = –4 mA	1.65 V	1.2			
	I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA	2.3 V	1.7			
		2.7 V	2.2			
		3 V	2.4			
	I _{OH} = –24 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 4 mA	1.65 V	0.45			
	I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA	2.3 V	0.7			
		2.7 V	0.4			
	I _{OL} = 24 mA	3 V	0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ} [§]	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3		pF
C _{i0}	A or B ports	V _O = V _{CC} or GND	3.3 V	7.5		pF
C ₀	ERR ports	V _O = V _{CC} or GND	3.3 V	6		pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.



timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency		†		125		125		125		MHz
t _w	Pulse duration	CLK↑	†		3		3		3		ns
		LE high	†		3		3		3		
t _{su}	Setup time	A, APAR or B, BPAR before CLK↑	†		1.9		2		1.7		ns
		CLKEN before CLK↑	†		2.1		2.1		1.7		
		A, APAR or B, BPAR before LE↓	†		1.4		1.3		1.2		
t _h	Hold time	A, APAR or B, BPAR after CLK↑	†		0.4		0.4		0.5		ns
		CLKEN after CLK↑	†		0.5		0.5		0.7		
		A, APAR or B, BPAR after LE↓	†		0.9		1.1		0.9		

† This information was not available at the time of publication.

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		125		125		125		MHz
t _{pd}	A or B	B or A		†	1	5.2		4.8	1	4.4	ns
		BPAR or APAR		†	2	8.9		7.6	2	6.7	
	APAR or BPAR	BPAR or APAR		†	1	5.7		5.2	1	4.7	
		ERRA or ERRB		†	2	9.7		8.7	2	7.5	
	ODD/EVEN	ERRA or ERRB		†	1.5	8.7		7.9	1.5	6.8	
		BPAR or APAR		†	1.5	8.3		7.6	1.5	6.5	
	SEL	BPAR or APAR		†	1	6.1		5.9	1	5.1	
	CLKAB or CLKBA	A or B		†	1	6.4		5.8	1	5.1	
		BPAR or APAR parity feedthrough		†	1.5	7.1		6.3	1.5	5.6	
		BPAR or APAR parity generated		†	2.5	10.2		8.7	2	7.7	
		ERRA or ERRB		†	2.5	10.5		8.9	2	7.9	
	LEAB or LEBA	A or B		†	1	6		5.5	1	4.8	
		BPAR or APAR parity feedthrough		†	1.5	6.7		6	1.5	5.3	
		BPAR or APAR parity generated		†	2.5	9.8		8.3	2	7.4	
		ERRA or ERRB		†	2.5	9.9		8.5	2	7.5	
t _{en}	OEAB or OEBA	B, BPAR or A, APAR		†	1.4	6.3		6.1	1	5.3	ns
t _{dis}	OEAB or OEBA	B, BPAR or A, APAR		†	1.3	6.1		5.2	1.5	4.9	ns
t _{en}	OEAB or OEBA	ERRA or ERRB		†	1.4	6.2		5.5	1	4.9	ns
t _{dis}	OEAB or OEBA	ERRA or ERRB		†	1.3	7.3		6.5	1	5.7	ns
t _{en}	SEL	ERRA or ERRB		†	1.4	6.7		6.5	1	5.5	ns
t _{dis}	SEL	ERRA or ERRB		†	1.3	6.4		5.4	1.5	4.9	ns

† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

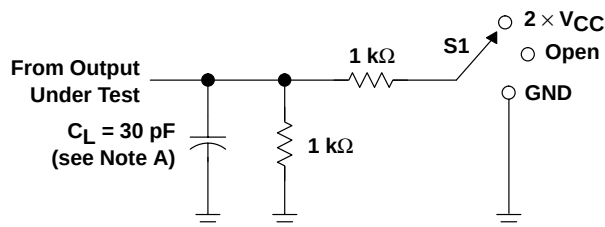
PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 50 pF, f = 10 MHz	†	22	27	pF
		Outputs disabled		†	5	8	

† This information was not available at the time of publication.



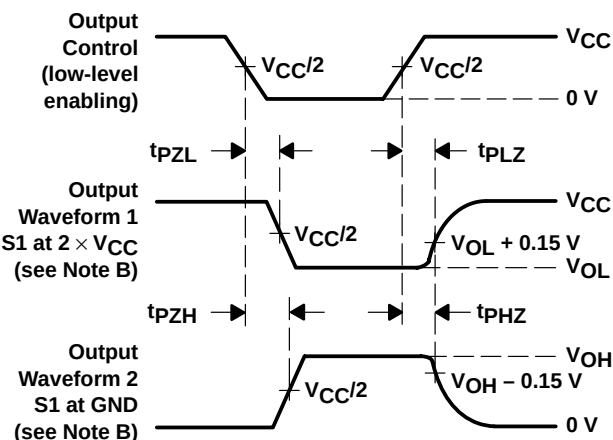
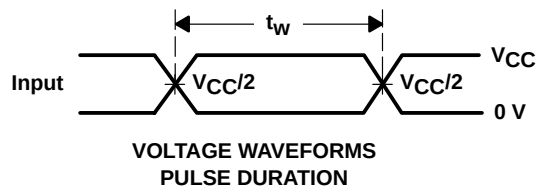
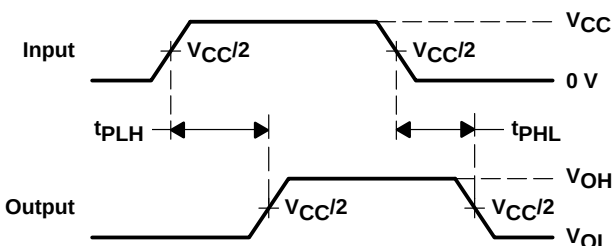
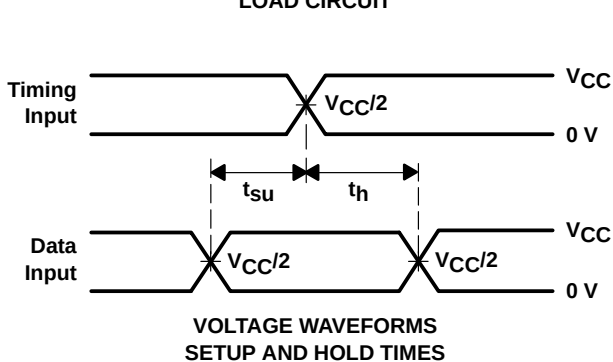
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

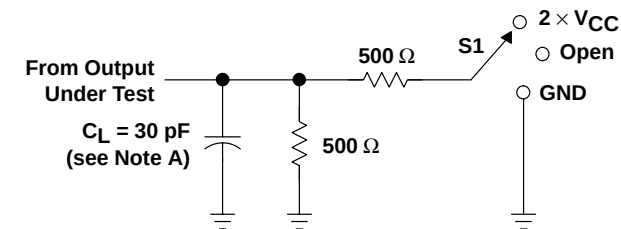
SN74ALVCH16901

18-BIT UNIVERSAL BUS TRANSCEIVER WITH PARITY GENERATORS/CHECKERS

SCES010E – JULY 1995 – REVISED FEBRUARY 1999

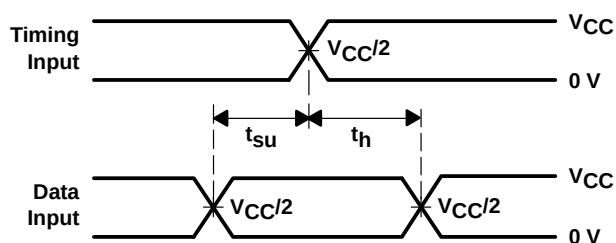
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

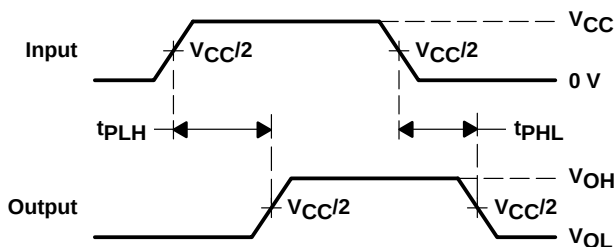


LOAD CIRCUIT

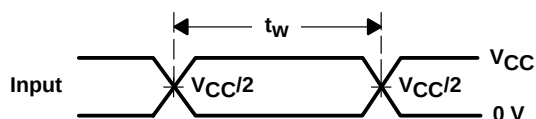
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



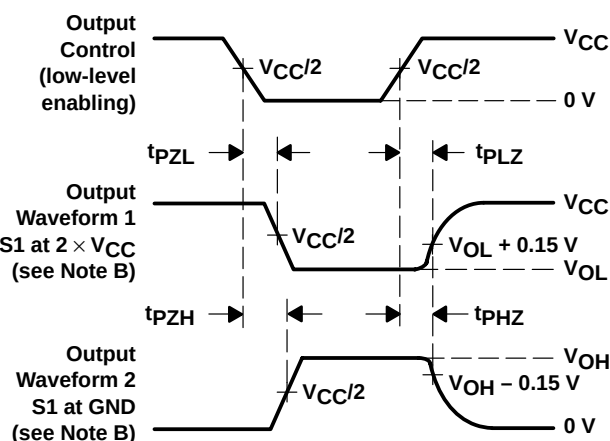
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION

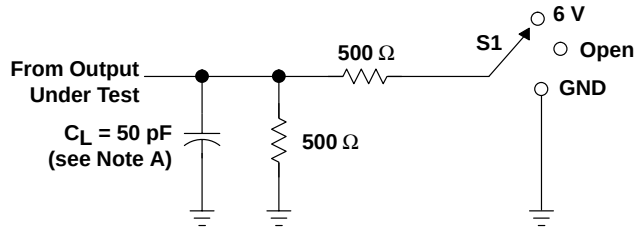


VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

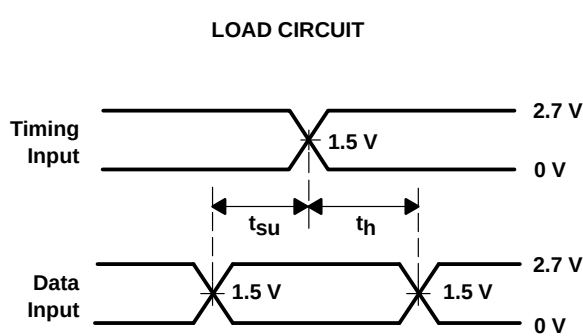
Figure 2. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

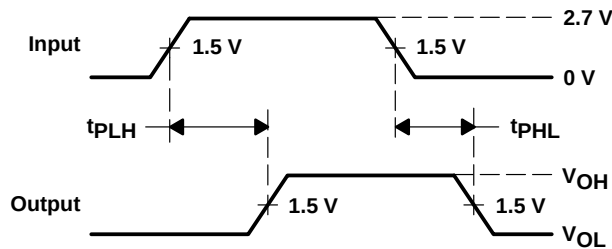


LOAD CIRCUIT

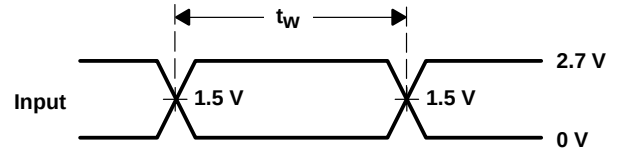
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



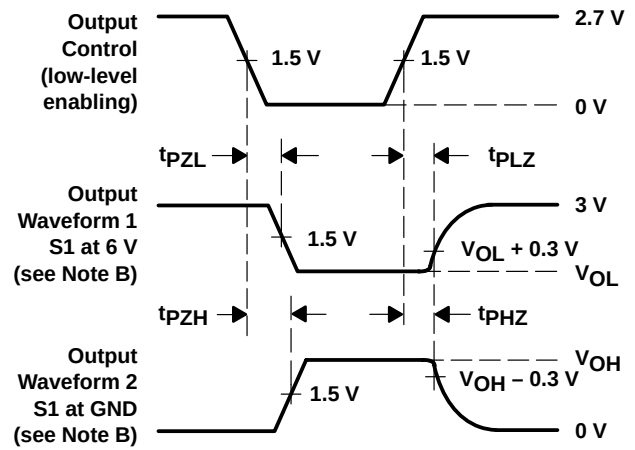
**VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES**



**VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES**



**VOLTAGE WAVEFORMS
PULSE DURATION**



**VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES**

- NOTES: A. C_L includes probe and jig capacitance.
 B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 D. The outputs are measured one at a time with one transition per measurement.
 E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 F. t_{PZL} and t_{PZH} are the same as t_{en} .
 G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH16952 16-BIT REGISTERED TRANSCEIVER WITH 3-STATE OUTPUTS

SCES011D – JULY 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 500 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages

description

This 16-bit registered transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

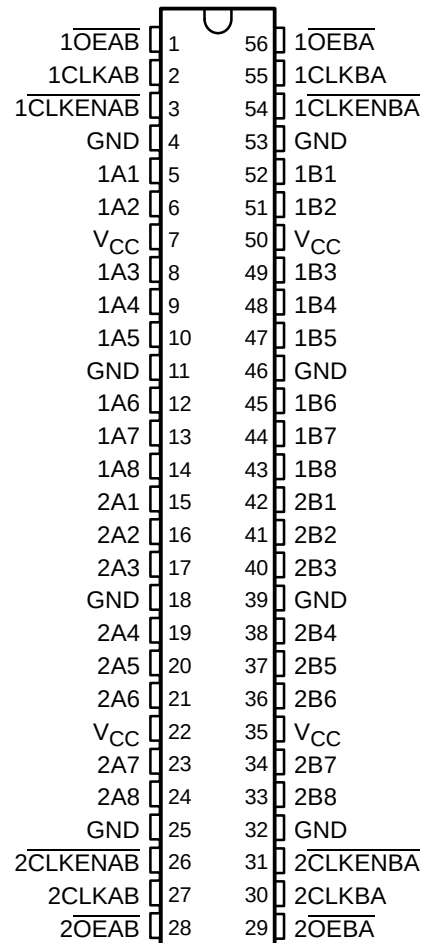
The SN74ALVCH16952 contains two sets of D-type flip-flops for temporary storage of data flowing in either direction. This device can be used as two 8-bit transceivers or one 16-bit transceiver. Data on the A or B bus is stored in the registers on the low-to-high transition of the clock (CLKAB or CLKBA) input provided that the clock-enable ($\overline{\text{CLKENAB}}$ or $\overline{\text{CLKENBA}}$) input is low. Taking the output-enable ($\overline{\text{OEAB}}$ or $\overline{\text{OEBA}}$) input low accesses the data on either port.

To ensure the high-impedance state during power up or power down, $\overline{\text{OE}}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16952 is characterized for operation from -40°C to 85°C .

DGG, DGV, OR DL PACKAGE
(TOP VIEW)



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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SN74ALVCH16952

16-BIT REGISTERED TRANSCEIVER WITH 3-STATE OUTPUTS

SCES011D – JULY 1995 – REVISED FEBRUARY 1999

FUNCTION TABLE[†]

INPUTS				OUTPUT B
CLKENAB	CLKAB	OEAB	A	
H	X	L	X	B ₀ [‡]
X	L	L	X	B ₀ [‡]
L	↑	L	L	L
L	↑	L	H	H
X	X	H	X	Z

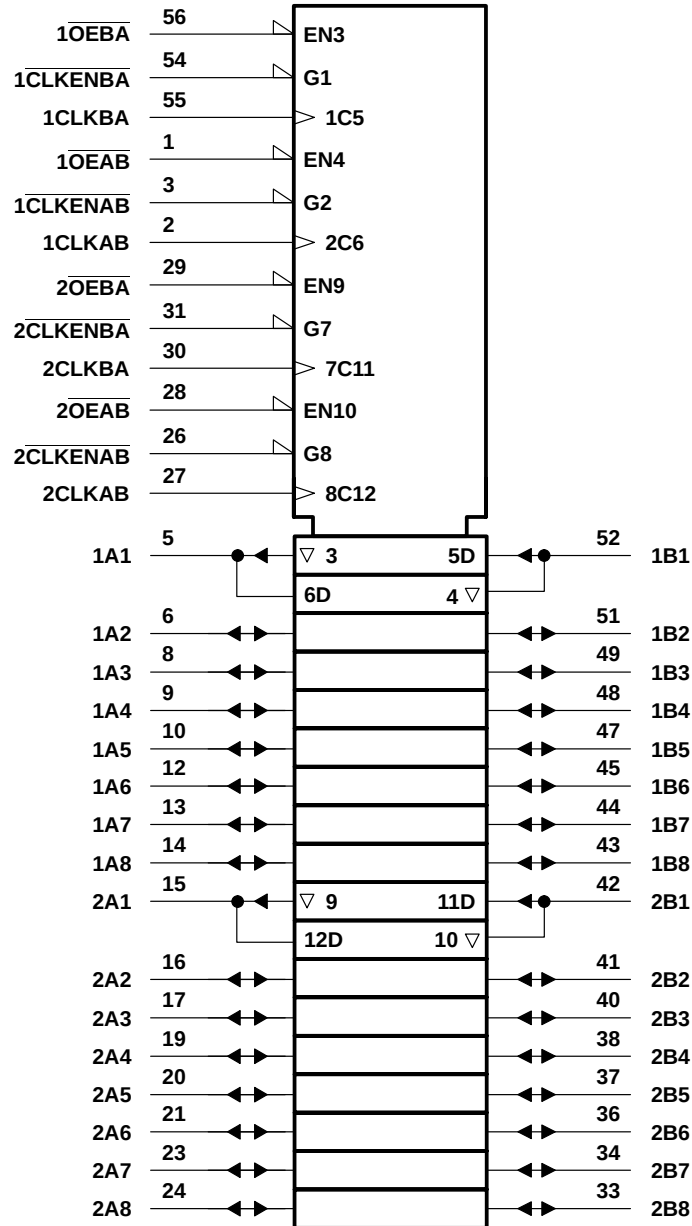
[†] A-to-B data flow is shown; B-to-A data flow is similar, but uses CLKENBA, CLKBA, and OEBA.

[‡] Level of B before the indicated steady-state input conditions were established

SN74ALVCH16952
16-BIT REGISTERED TRANSCEIVER
WITH 3-STATE OUTPUTS

SCES011D – JULY 1995 – REVISED FEBRUARY 1999

logic symbol[†]



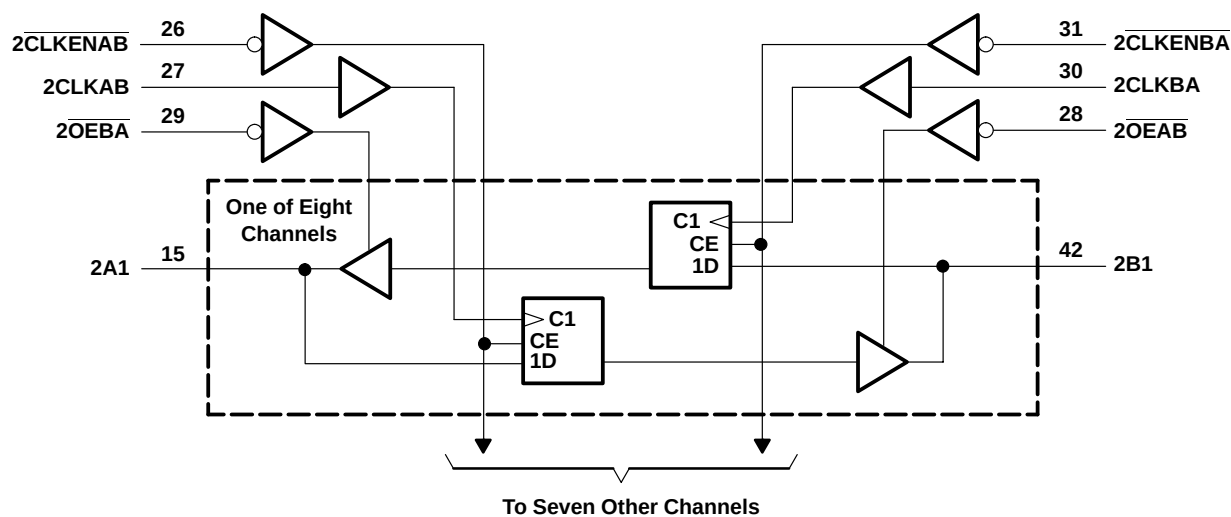
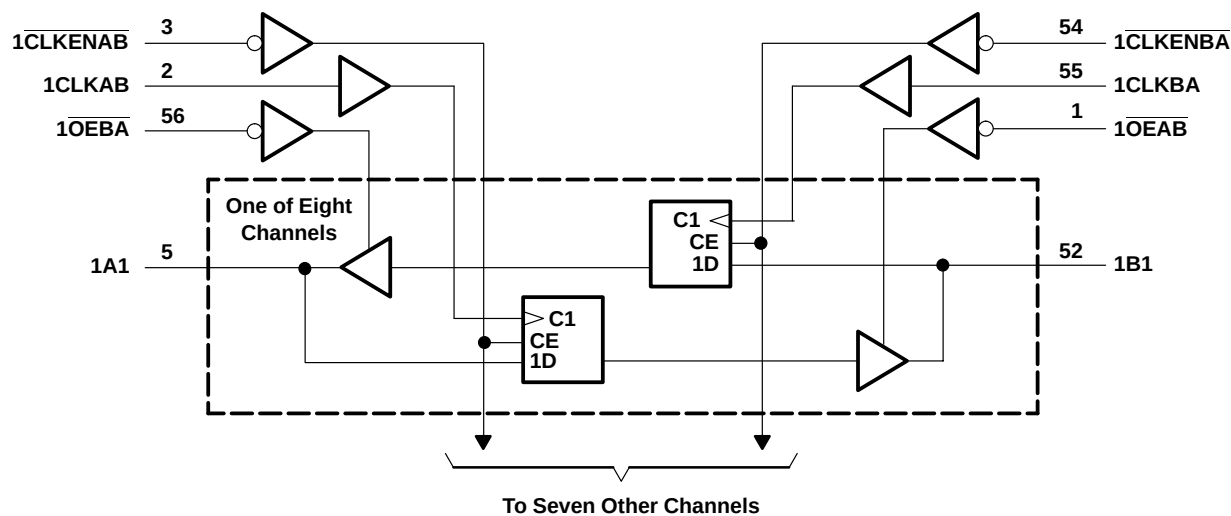
[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

SN74ALVCH16952

16-BIT REGISTERED TRANSCEIVER WITH 3-STATE OUTPUTS

SCES011D – JULY 1995 – REVISED FEBRUARY 1999

logic diagram (positive logic)



SN74ALVCH16952

16-BIT REGISTERED TRANSCEIVER WITH 3-STATE OUTPUTS

SCES011D – JULY 1995 – REVISED FEBRUARY 1999

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = −100 μA	1.65 V to 3.6 V	V _{CC} −0.2			V
		I _{OH} = −4 mA	1.65 V	1.2			
		I _{OH} = −6 mA	2.3 V	2			
	I _{OH} = −12 mA		2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
	I _{OH} = −24 mA	3 V	2				
V _{OL}		I _{OL} = 100 μA	1.65 V to 3.6 V			0.2	V
		I _{OL} = 4 mA	1.65 V			0.45	
		I _{OL} = 6 mA	2.3 V			0.4	
	I _{OL} = 12 mA		2.3 V			0.7	
			2.7 V			0.4	
	I _{OL} = 24 mA	3 V			0.55		
I _I	V _I = V _{CC} or GND		3.6 V			±5	μA
I _I (hold)		V _I = 0.58 V	1.65 V	25			μA
		V _I = 1.07 V	1.65 V	−25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	−45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	−75			
		V _I = 0 to 3.6 V [‡]	3.6 V			±500	
I _{OZ} [§]	V _O = V _{CC} or GND		3.6 V			±10	μA
I _{CC}	V _I = V _{CC} or GND, I _O = 0		3.6 V			40	μA
ΔI _{CC}		One input at V _{CC} − 0.6 V, Other inputs at V _{CC} or GND		3 V to 3.6 V		750	μA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3.5			pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V	8.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency		¶		150		150		150		MHz
t _w	Pulse duration	CLKEN high	¶		3.3		3.3		3.3		ns
		CLK high or low	¶		3.3		3.3		3.3		
t _{su}	Setup time	Data before CLK	¶		1.7		1.9		1.5		ns
		CLKEN before CLK	¶		1.2		1		1		
t _h	Hold time	Data after CLK	¶		0.6		0.6		0.8		ns
		CLKEN after CLK	¶		1.1		0.9		1.1		

† This information was not available at the time of publication.



SN74ALVCH16952
16-BIT REGISTERED TRANSCEIVER
WITH 3-STATE OUTPUTS

SCES011D – JULY 1995 – REVISED FEBRUARY 1999

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	CLK	A or B	†		1	4.1	4.6		1	3.9	ns
t _{en}	$\overline{\text{OEBA}}$ or $\overline{\text{OEAB}}$	A or B	†		1	5.4	5.3		1	4.4	ns
t _{dis}	$\overline{\text{OEBA}}$ or $\overline{\text{OEAB}}$	A or B	†		1	5.3	4.4		1.1	4	ns

† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 0, f = 10 MHz	†	53	71	pF
		Outputs disabled		†	34	40	

† This information was not available at the time of publication.



SN74ALVCH16952

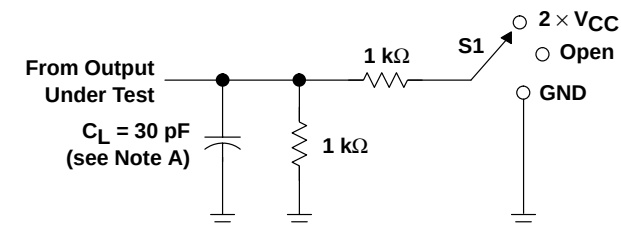
16-BIT REGISTERED TRANSCEIVER

WITH 3-STATE OUTPUTS

SCES011D – JULY 1995 – REVISED FEBRUARY 1999

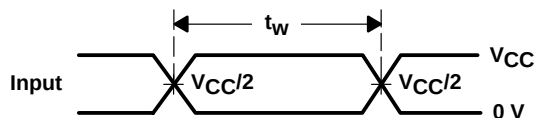
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8\text{ V}$

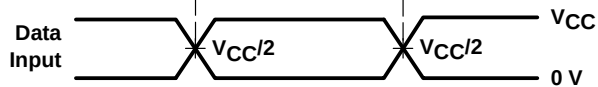


LOAD CIRCUIT

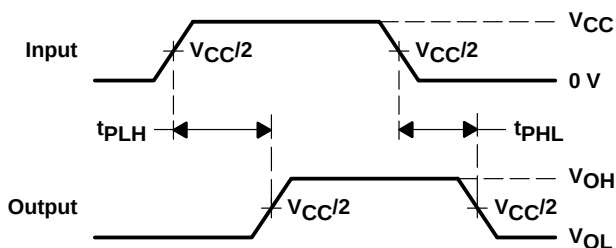
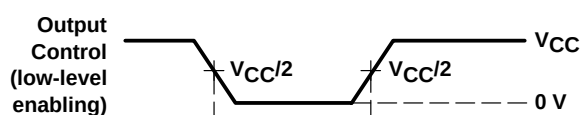
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PHL}	GND



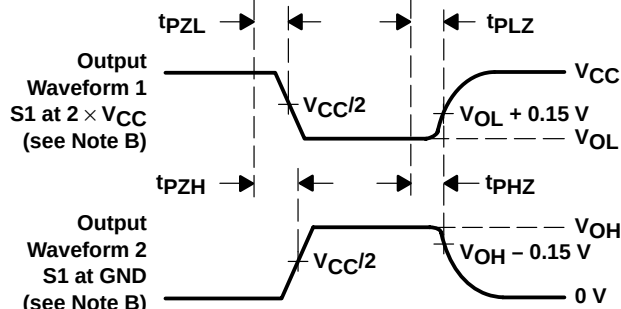
VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



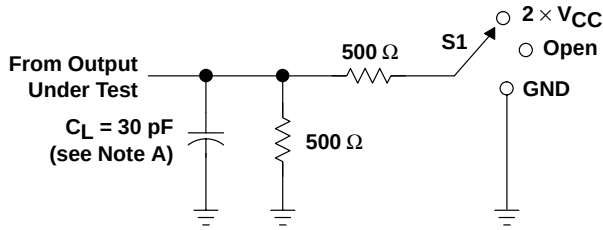
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

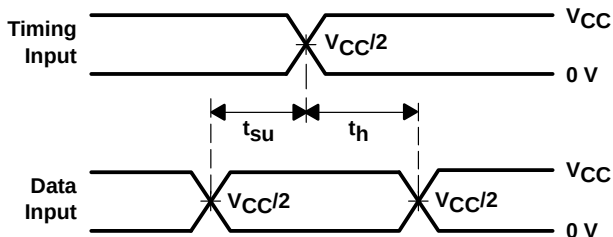
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

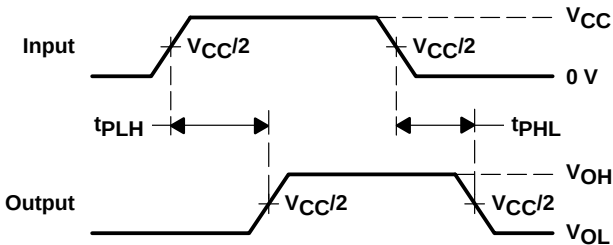


LOAD CIRCUIT

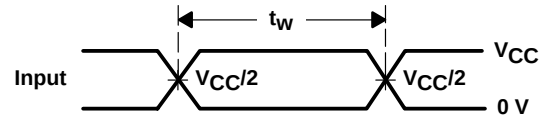
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



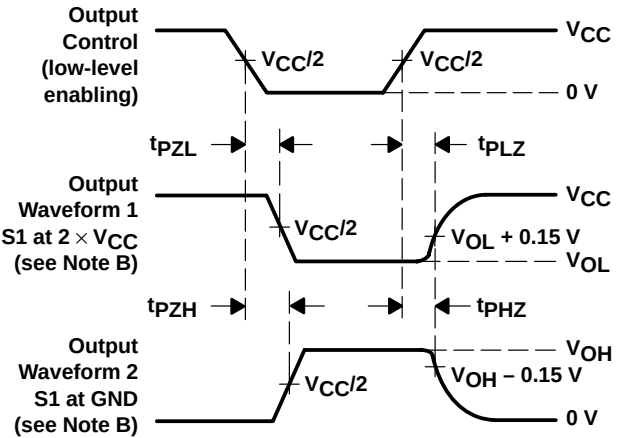
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH16952

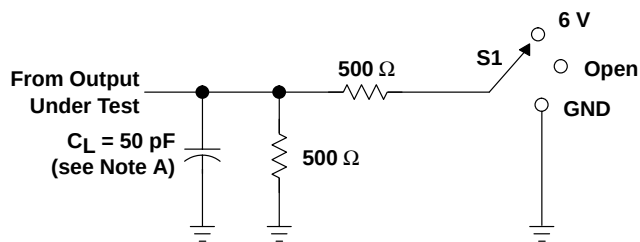
16-BIT REGISTERED TRANSCEIVER

WITH 3-STATE OUTPUTS

SCES011D – JULY 1995 – REVISED FEBRUARY 1999

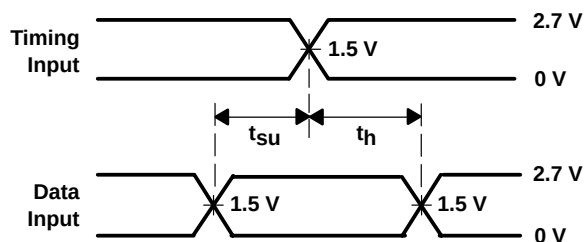
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$

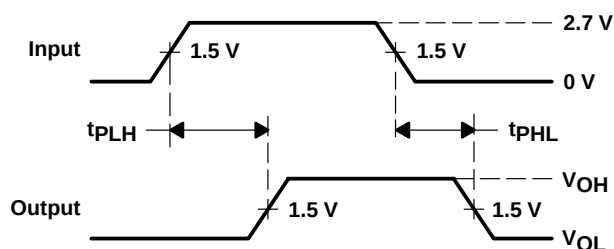


LOAD CIRCUIT

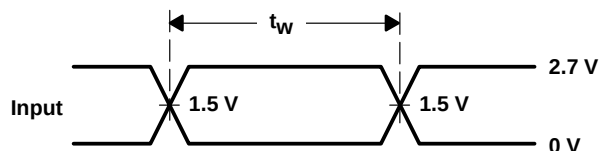
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



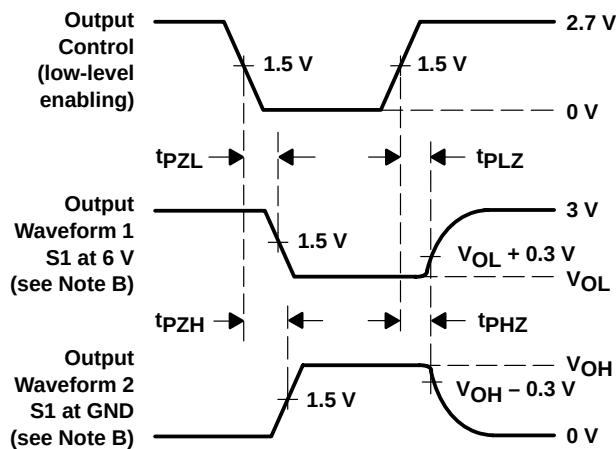
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH32501

36-BIT UNIVERSAL BUS TRANSCEIVER WITH 3-STATE OUTPUTS

SCES144A – OCTOBER 1998 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- *UBT*™ (Universal Bus Transceiver) Combines D-Type Latches and D-Type Flip-Flops for Operation in Transparent, Latched, or Clocked Mode
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Packaged in Plastic Fine-Pitch Ball Grid Array Package

description

This 36-bit universal bus transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

This device can be used as two 18-bit transceivers or one 36-bit transceiver. Data flow in each direction is controlled by output-enable ($\overline{OEAB}$ and $\overline{OEBA}$), latch-enable ($\overline{LEAB}$ and $\overline{LEBA}$), and clock ($\overline{CLKAB}$ and $\overline{CLKBA}$) inputs. For A-to-B data flow, the device operates in the transparent mode when $\overline{LEAB}$ is high. When $\overline{LEAB}$ is low, the A data is latched if $\overline{CLKAB}$ is held at a high or low logic level. If $\overline{LEAB}$ is low, the A data is stored in the latch/flip-flop on the low-to-high transition of $\overline{CLKAB}$. When $\overline{OEAB}$ is high, the outputs are active. When $\overline{OEAB}$ is low, the outputs are in the high-impedance state.

Data flow for B to A is similar to that of A to B but uses $\overline{OEBA}$, $\overline{LEBA}$, and $\overline{CLKBA}$. The output enables are complementary ($\overline{OEAB}$ is active high and $\overline{OEBA}$ is active low).

To ensure the high-impedance state during power up or power down, $\overline{OEBA}$ should be tied to V_{CC} through a pullup resistor and $\overline{OEAB}$ should be tied to GND through a pulldown resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH32501 is characterized for operation from -40°C to 85°C .

FUNCTION TABLE†

INPUTS				OUTPUT B
$\overline{OEAB}$	$\overline{LEAB}$	$\overline{CLKAB}$	A	
L	X	X	X	Z
H	H	X	L	L
H	H	X	H	H
H	L	↑	L	L
H	L	↑	H	H
H	L	L or H	X	$B_0^{\ddagger}$

† A-to-B data flow is shown; B-to-A flow is similar but uses $\overline{OEBA}$, $\overline{LEBA}$, and $\overline{CLKBA}$.

‡ Output level before the indicated steady-state input conditions were established, provided that $\overline{CLKAB}$ is high before $\overline{LEAB}$ goes low

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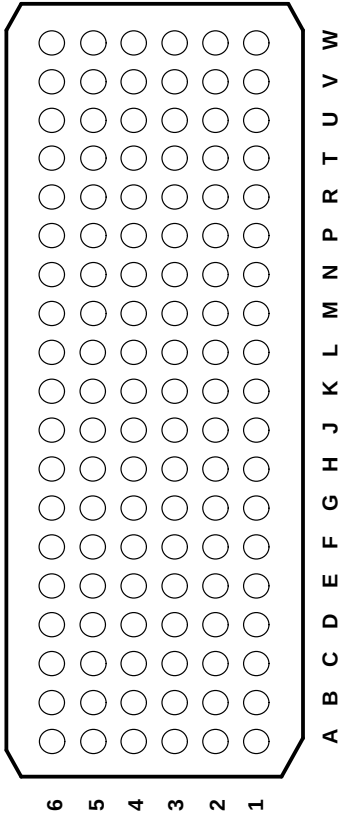
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GKF PACKAGE
(TOP VIEW)



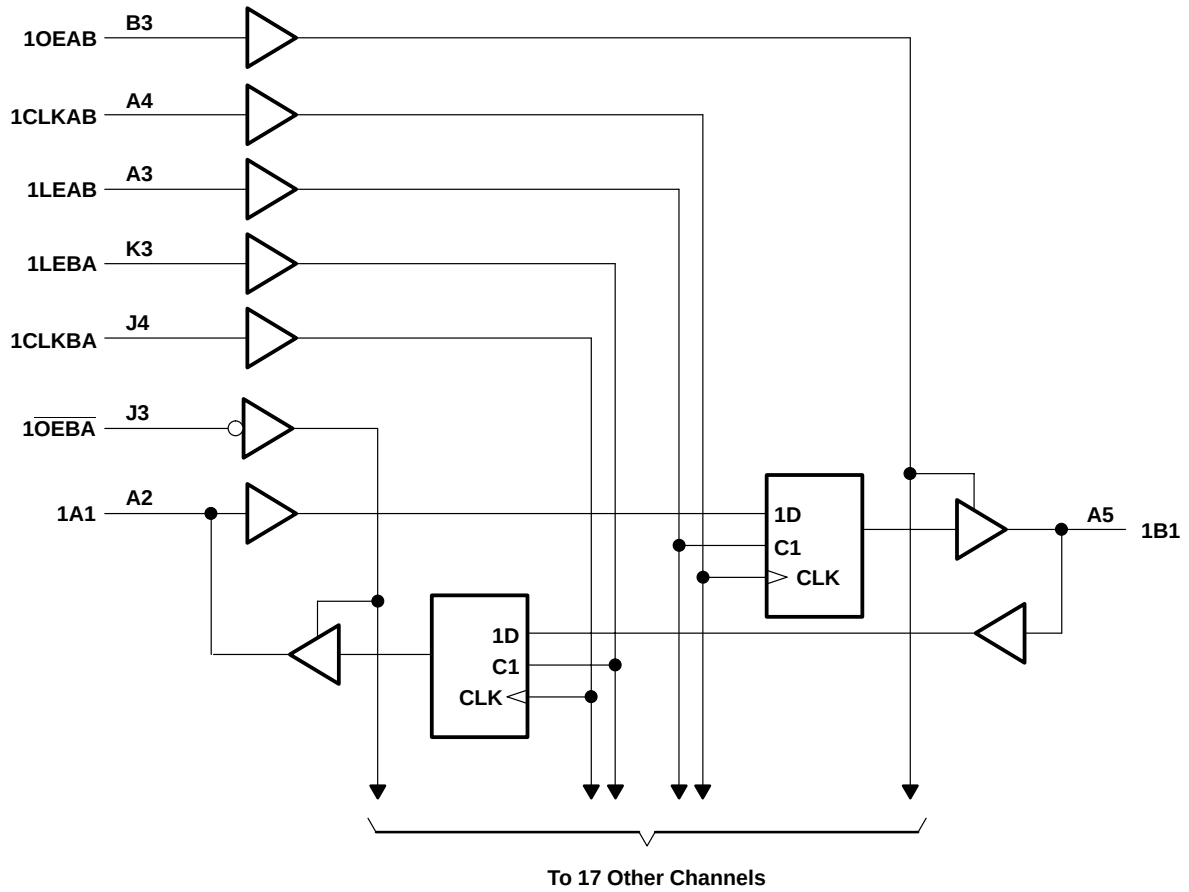
terminal assignments

6	1B2	1B4	1B6	1B8	1B10	1B12	1B14	1B15	1B17	NC	2B2	2B4	2B6	2B8	2B10	2B12
5	1B1	1B3	1B5	1B7	1B9	1B11	1B13	1B16	1B18	2CLKAB	2B1	2B3	2B5	2B7	2B9	2B11
4	1CLKAB	GND	GND	VCC	GND	GND	VCC	GND	1CLKBA	GND	GND	GND	VCC	GND	GND	VCC
3	1LEAB	1OEAB	GND	VCC	GND	GND	VCC	GND	1OEBA	1LEBA	2OEAB	GND	VCC	GND	GND	VCC
2	1A1	1A3	1A5	1A7	1A9	1A11	1A13	1A16	1A18	2LEAB	2A1	2A3	2A5	2A7	2A9	2A11
1	1A2	1A4	1A6	1A8	1A10	1A12	1A14	1A15	1A17	NC	2A2	2A4	2A6	2A8	2A10	2A12
	A	B	C	D	E	F	G	H	J	K	L	M	N	P	R	T

SN74ALVCH32501
36-BIT UNIVERSAL BUS TRANSCEIVER
WITH 3-STATE OUTPUTS

SCES144A – OCTOBER 1998 – REVISED FEBRUARY 1999

logic diagram (positive logic)



PRODUCT PREVIEW



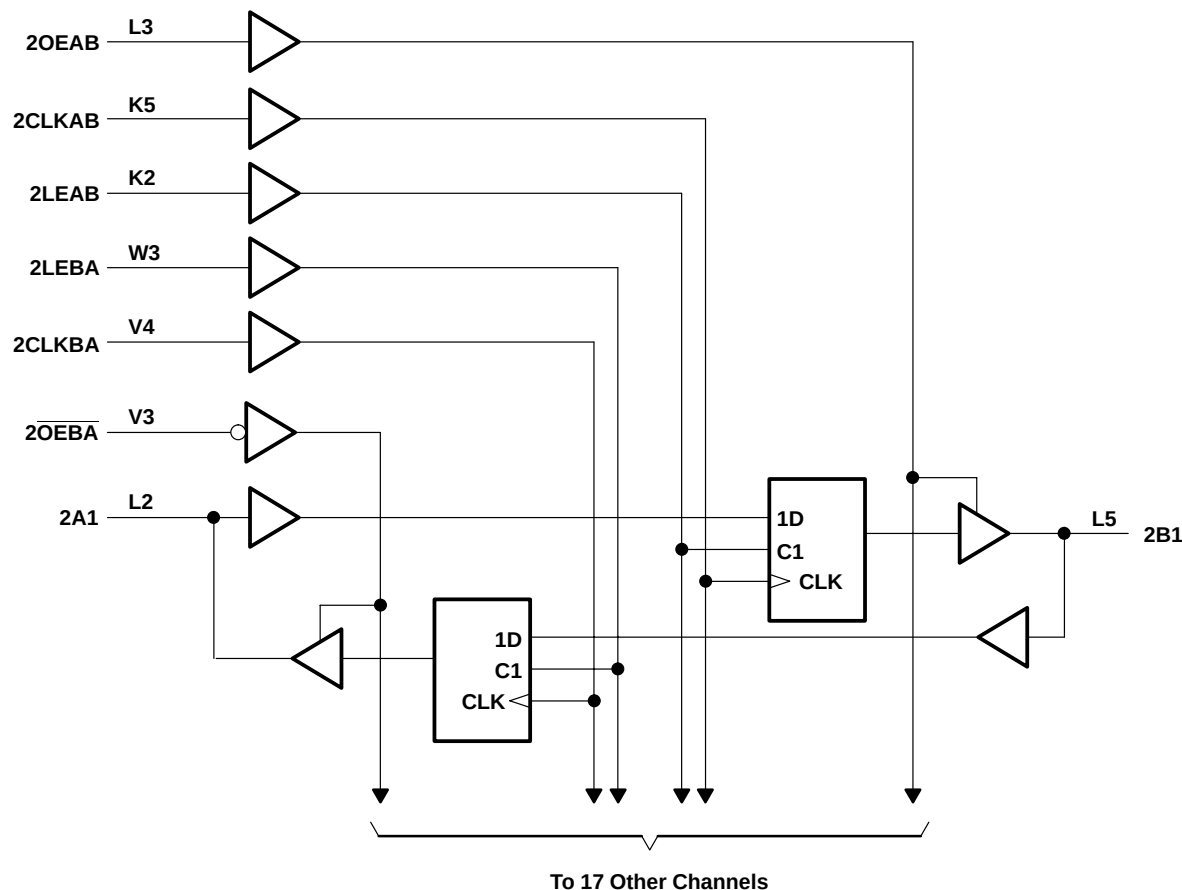
SN74ALVCH32501

36-BIT UNIVERSAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

SCES144A – OCTOBER 1998 – REVISED FEBRUARY 1999

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3)	39°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output-current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

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WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate			10	ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

PRODUCT PREVIEW



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36-BIT UNIVERSAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 μA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
	I _{OH} = –12 mA		2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
V _{OL}		I _{OL} = 100 μA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
	I _{OL} = 12 mA		2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
I _I		V _I = V _{CC} or GND	3.6 V	±5			μA
I _I (hold)		V _I = 0.58 V	1.65 V	25			μA
		V _I = 1.07 V		–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V		–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V		–75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
	I _{OZ} [§]	V _O = V _{CC} or GND	3.6 V	±10			
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	20			μA	
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			μA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V				pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V				pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.

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WITH 3-STATE OUTPUTS

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			$V_{CC} = 1.8\text{ V}$		$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f_{clock}	Clock frequency										MHz
t_w	Pulse duration	LE high									ns
		CLK high or low									
t_{su}	Setup time	Data before CLK $\uparrow$									ns
		Data before LE $\downarrow$	CLK high								
			CLK low								
t_h	Hold time	Data after CLK $\uparrow$									ns
		Data after LE $\downarrow$	CLK high or low								

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 1.8\text{ V}$		$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f_{max}											MHz
t_{pd}	A or B	B or A									ns
	LE	A or B									
	CLK										
t_{en}	OEAB	B									ns
t_{dis}	OEAB	B									ns
t_{en}	$\overline{\text{OEBA}}$	A									ns
t_{dis}	$\overline{\text{OEBA}}$	A									ns

operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER			TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
				TYP	TYP	TYP	
C_{pd}	Power dissipation capacitance	Outputs enabled	$C_L = 0, \quad f = 10\text{ MHz}$				pF
		Outputs disabled					

PRODUCT PREVIEW



SN74ALVCH32501

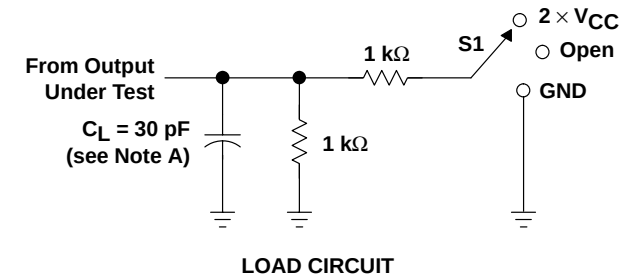
36-BIT UNIVERSAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

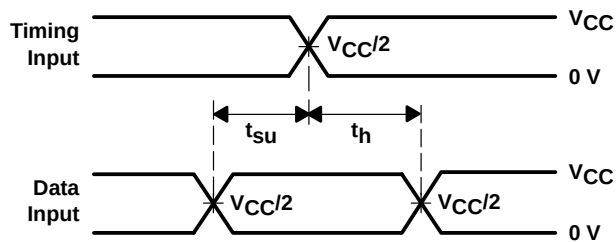
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PARAMETER MEASUREMENT INFORMATION

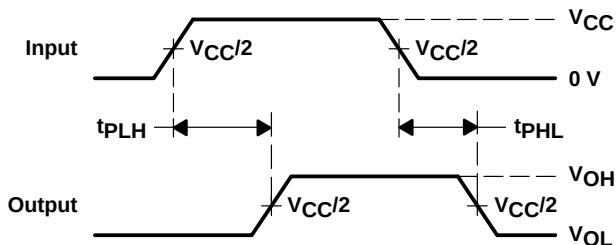
$V_{CC} = 1.8 \text{ V}$



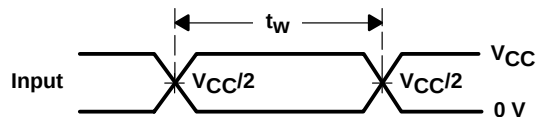
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



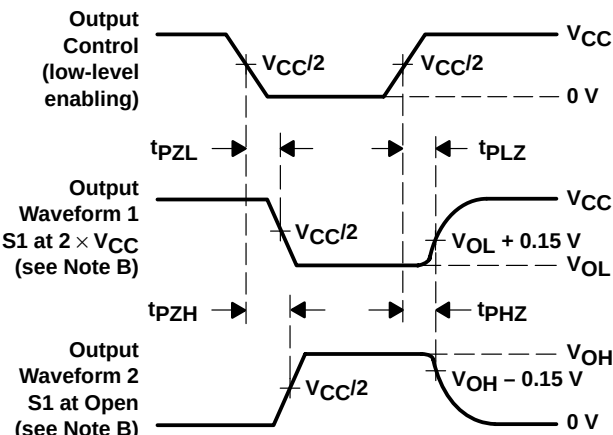
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



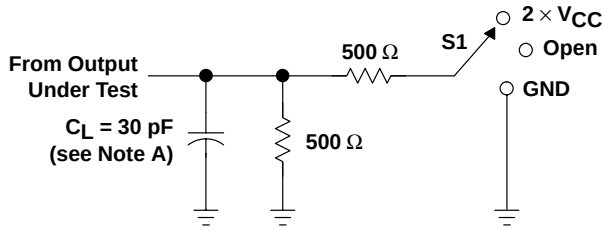
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

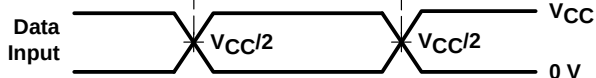
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

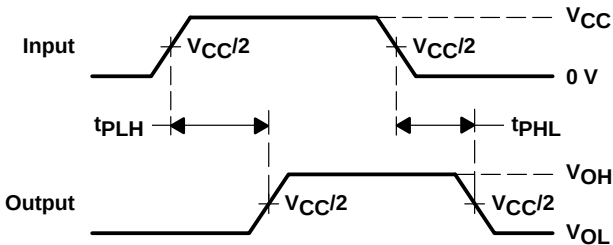


LOAD CIRCUIT

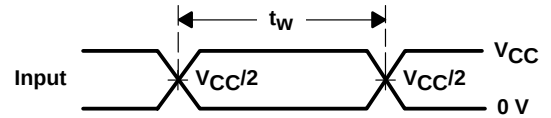
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



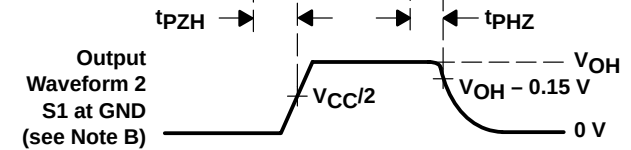
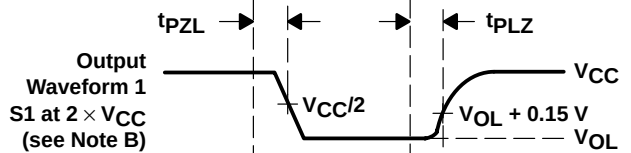
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
D. The outputs are measured one at a time with one transition per measurement.
E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
F. t_{PZL} and t_{PZH} are the same as t_{en} .
G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH32501

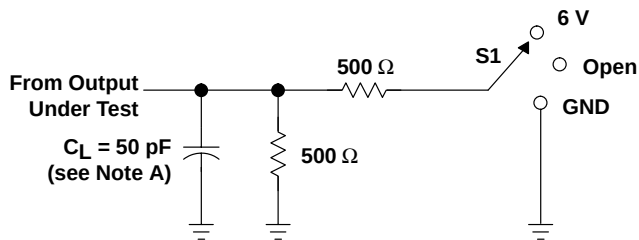
36-BIT UNIVERSAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

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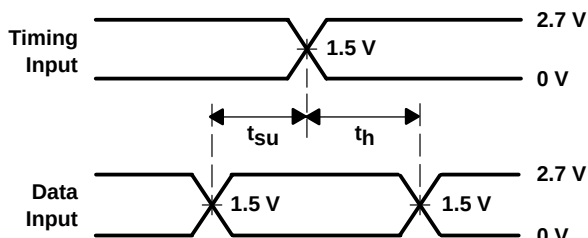
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

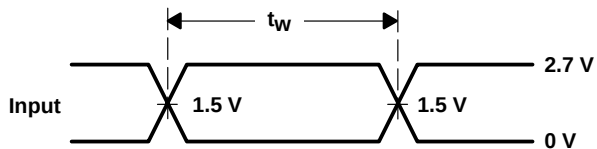


LOAD CIRCUIT

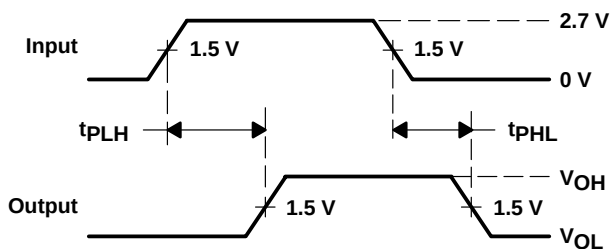
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



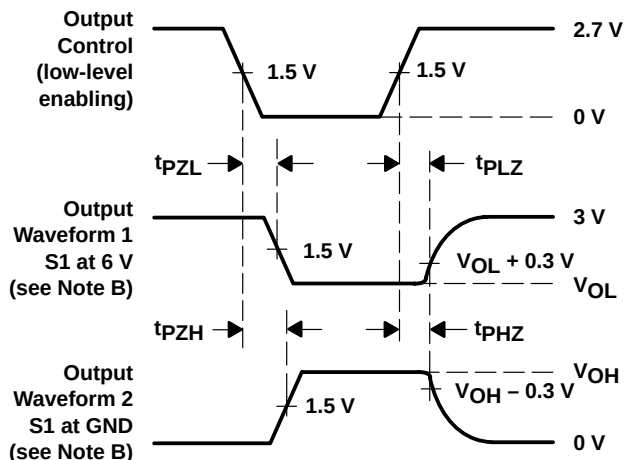
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

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SN74ALVCH162244

16-BIT BUFFER/DRIVER WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Output Ports Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 16-bit buffer/driver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH162244 is designed specifically to improve the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters.

The device can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. It provides true outputs and symmetrical active-low output-enable ($\overline{OE}$) inputs.

The outputs, which are designed to sink up to 12 mA, include equivalent 26-Ω resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH162244 is characterized for operation from –40°C to 85°C.

DGG OR DL PACKAGE
(TOP VIEW)

$\overline{1OE}$	1	48	$\overline{2OE}$
1Y1	2	47	1A1
1Y2	3	46	1A2
GND	4	45	GND
1Y3	5	44	1A3
1Y4	6	43	1A4
V_{CC}	7	42	V_{CC}
2Y1	8	41	2A1
2Y2	9	40	2A2
GND	10	39	GND
2Y3	11	38	2A3
2Y4	12	37	2A4
3Y1	13	36	3A1
3Y2	14	35	3A2
GND	15	34	GND
3Y3	16	33	3A3
3Y4	17	32	3A4
V_{CC}	18	31	V_{CC}
4Y1	19	30	4A1
4Y2	20	29	4A2
GND	21	28	GND
4Y3	22	27	4A3
4Y4	23	26	4A4
$\overline{4OE}$	24	25	$\overline{3OE}$

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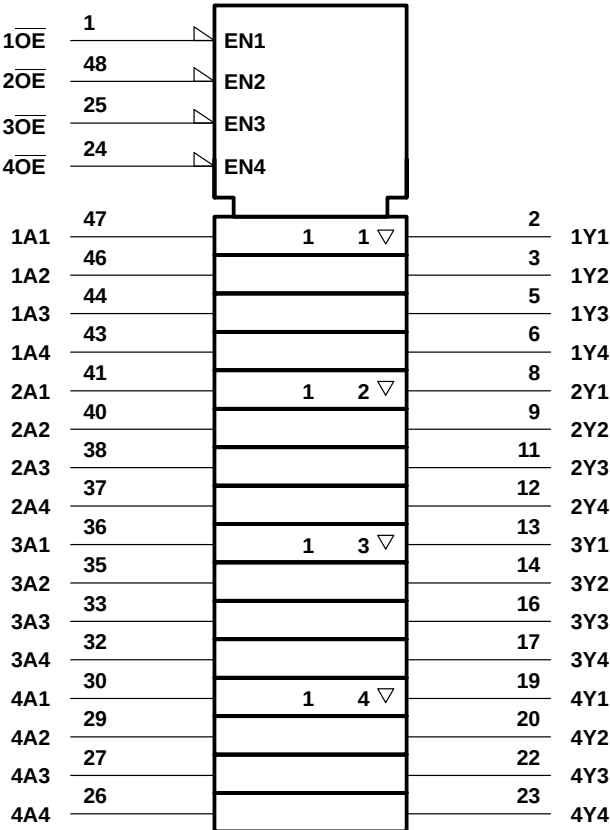
SN74ALVCH162244
16-BIT BUFFER/DRIVER
WITH 3-STATE OUTPUTS

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FUNCTION TABLE
(each 4-bit buffer)

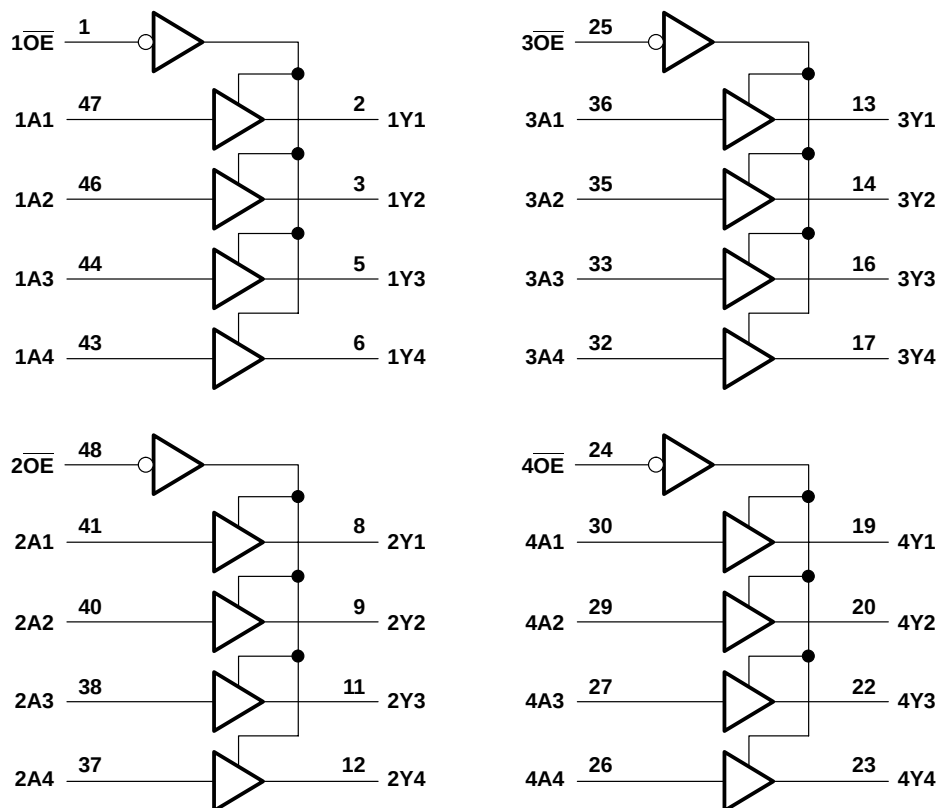
INPUTS		OUTPUT Y
OE	A	
L	H	H
L	L	L
H	X	Z

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	89°C/W
DL package	94°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

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16-BIT BUFFER/DRIVER
WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–2	mA
		$V_{CC} = 2.3 \text{ V}$	–6	
		$V_{CC} = 2.7 \text{ V}$	–8	
		$V_{CC} = 3 \text{ V}$	–12	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	2	mA
		$V_{CC} = 2.3 \text{ V}$	6	
		$V_{CC} = 2.7 \text{ V}$	8	
		$V_{CC} = 3 \text{ V}$	12	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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16-BIT BUFFER/DRIVER
WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V			±5	µA
I _I (hold)		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V			±500	
I _{OZ}		V _O = V _{CC} or GND	3.6 V			±10	µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V			40	µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V			750	µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3			pF
	Data inputs			6			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	Y	§	1	4.9	4.7		1	4.2	ns
t _{en}	OE	Y	§	1	6.8	6.7		1	5.6	ns
t _{dis}	OE	Y	§	1	6.3	5.7		1	5.5	ns

§ This information was not available at the time of publication.



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16-BIT BUFFER/DRIVER
WITH 3-STATE OUTPUTS

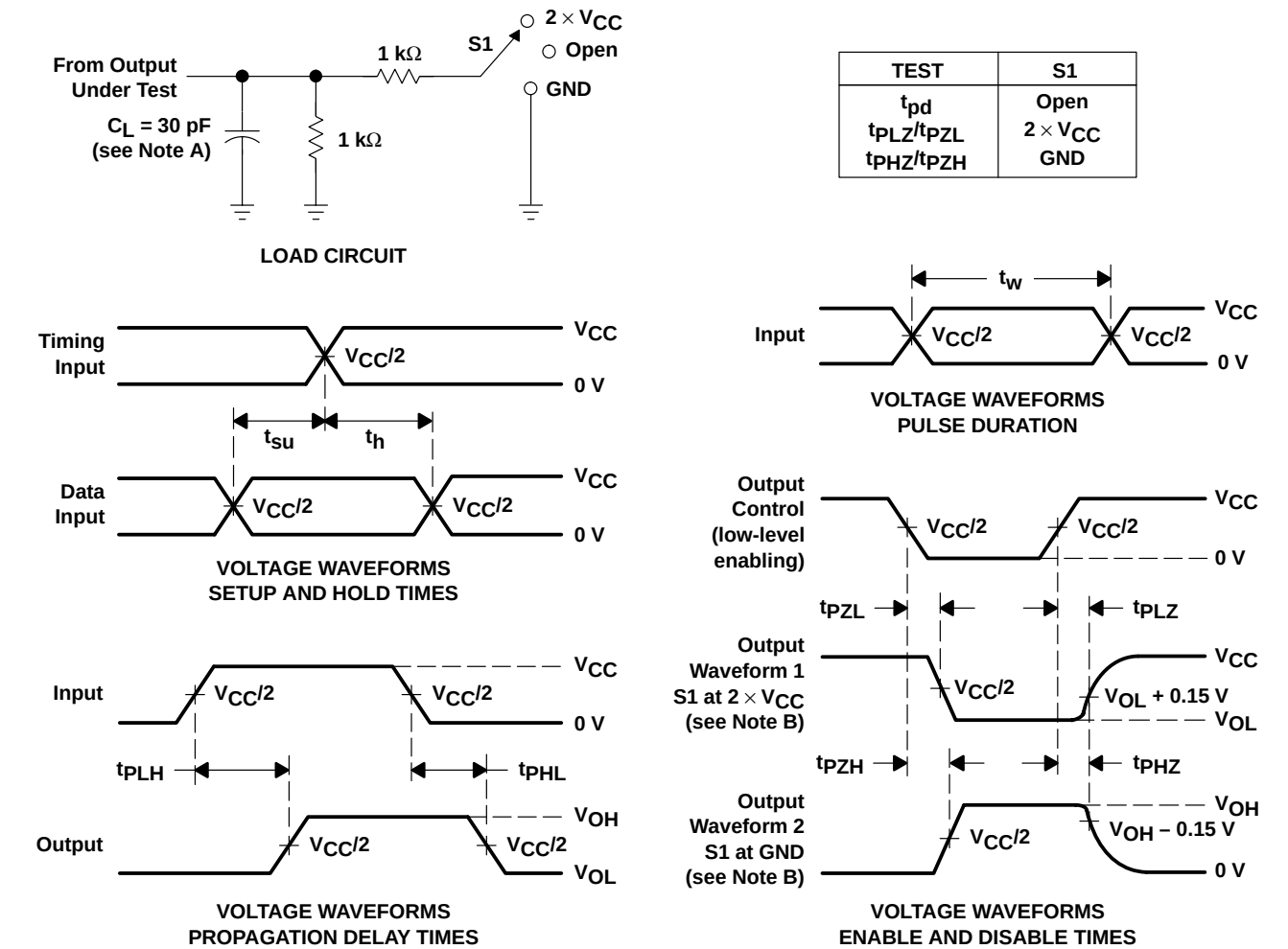
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operating characteristics, $T_A = 25^{\circ}\text{C}$

PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd} Power dissipation capacitance	Outputs enabled	$C_L = 50\text{ pF}, f = 10\text{ MHz}$	†	16	19	pF
	Outputs disabled		†	4	5	

† This information was not available at the time of publication.

PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8\text{ V}$

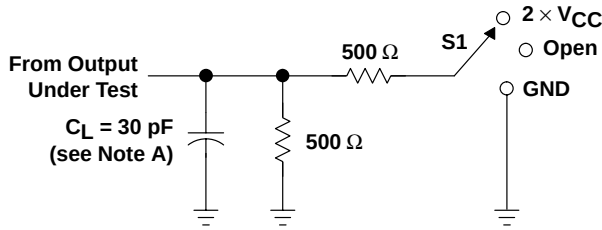


- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

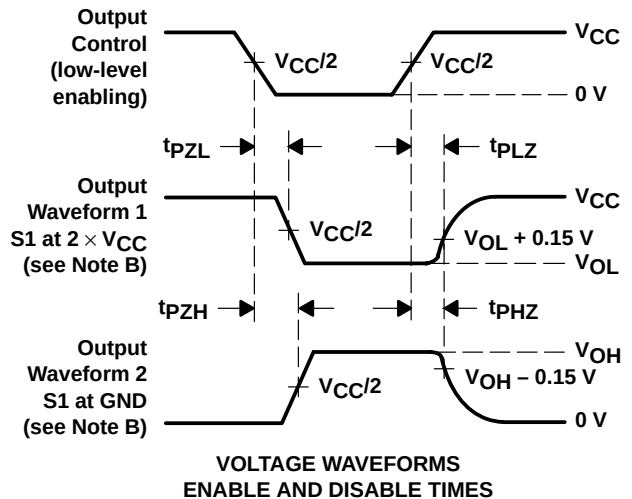
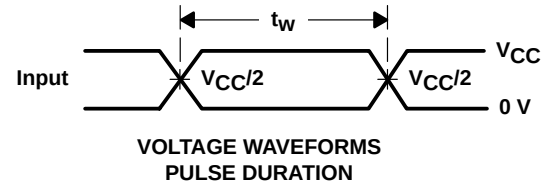
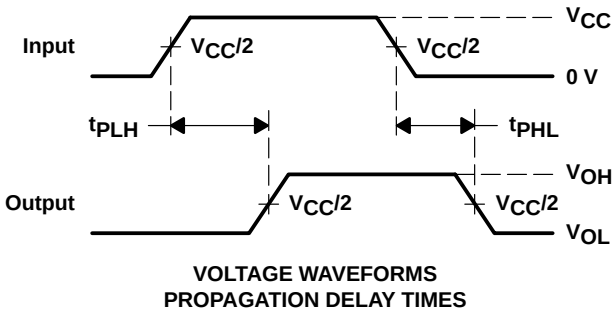
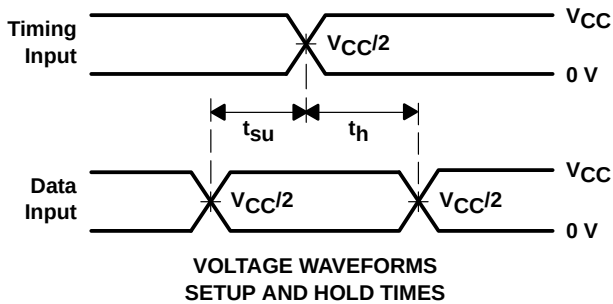
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
D. The outputs are measured one at a time with one transition per measurement.
E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
F. t_{PZL} and t_{PZH} are the same as t_{en} .
G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH162244

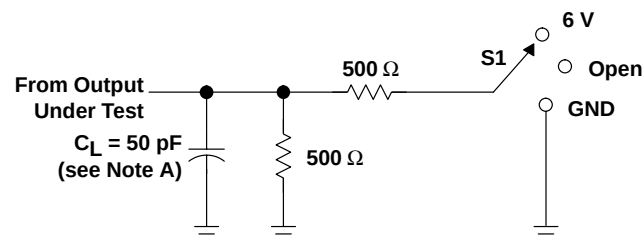
16-BIT BUFFER/DRIVER

WITH 3-STATE OUTPUTS

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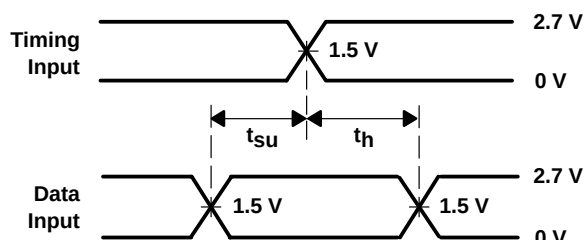
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

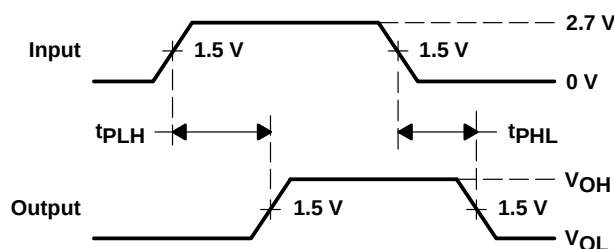


LOAD CIRCUIT

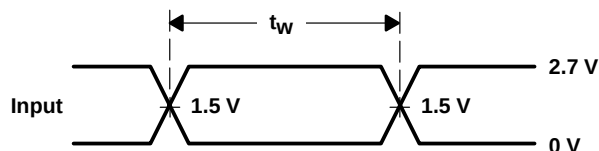
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



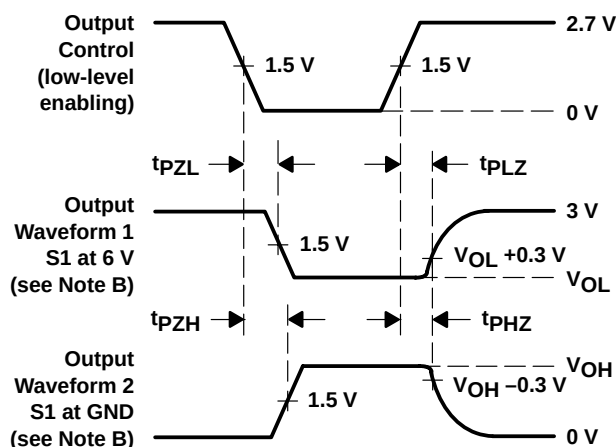
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCHR162245

16-BIT BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- All Outputs Have Equivalent 26- Ω Series Resistors, So No External Resistors Are Required
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

NOTE: For order entry:
The DGG package is abbreviated to G.

description

This 16-bit (dual-octal) noninverting bus transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCHR162245 is designed for asynchronous communication between data buses. The control-function implementation minimizes external timing requirements.

This device can be used as two 8-bit transceivers or one 16-bit transceiver. It allows data transmission from the A bus to the B bus or from the B bus to the A bus, depending on the logic level at the direction-control (DIR) input. The output-enable ($\overline{OE}$) input can be used to disable the device so that the buses are effectively isolated.

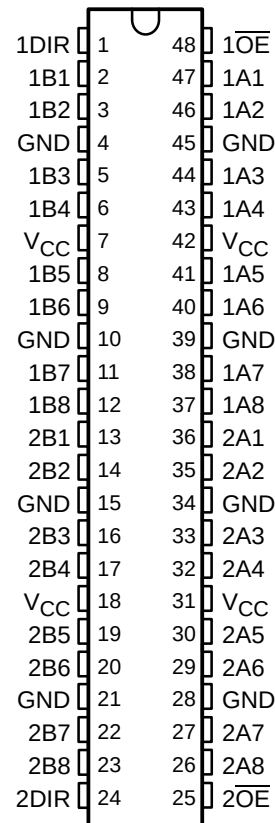
All outputs, which are designed to sink up to 12 mA, include equivalent 26- Ω series resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCHR162245 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)



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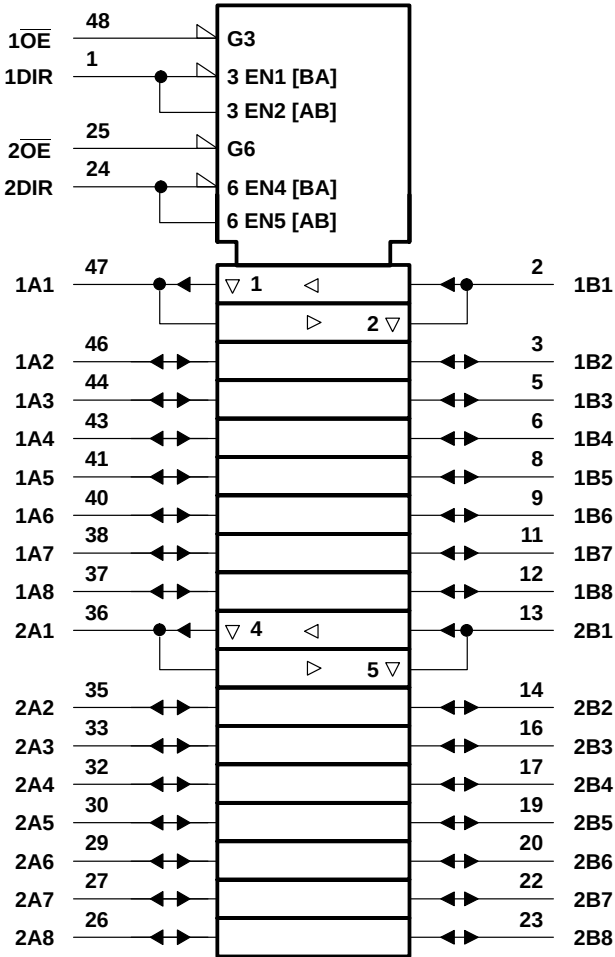
SN74ALVCHR162245
16-BIT BUS TRANSCEIVER
WITH 3-STATE OUTPUTS

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FUNCTION TABLE
(each 8-bit section)

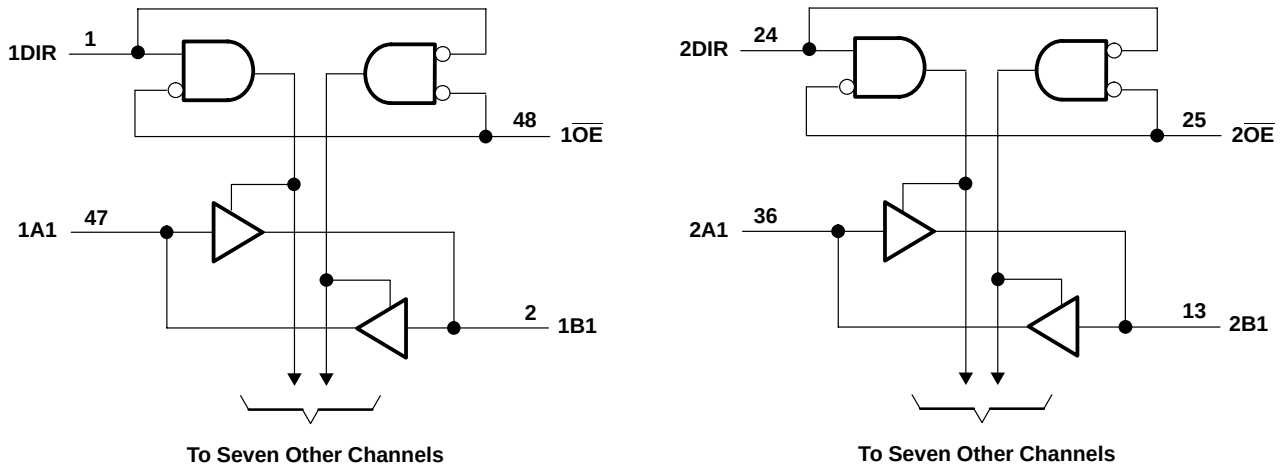
INPUTS		OPERATION
OE	DIR	
L	L	B data to A bus
L	H	A data to B bus
H	X	Isolation

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	89°C/W
DL package	94°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

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16-BIT BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–2	mA
		$V_{CC} = 2.3 \text{ V}$	–6	
		$V_{CC} = 2.7 \text{ V}$	–8	
		$V_{CC} = 3 \text{ V}$	–12	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	2	mA
		$V_{CC} = 2.3 \text{ V}$	6	
		$V_{CC} = 2.7 \text{ V}$	8	
		$V_{CC} = 3 \text{ V}$	12	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V			±5	µA
I _I (hold)		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V		–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V		–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V		–75			
		V _I = 0 to 3.6 V [‡]	3.6 V			±500	
I _{OZ} [§]		V _O = V _{CC} or GND	3.6 V			±10	µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V			40	µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V			750	µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V			4	pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V			9	pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A or B	B or A	¶	1	4.9	4.7		1	4.2	ns
t _{en}	$\overline{\text{OE}}$	B or A	¶	1	6.8	6.7		1	5.6	ns
t _{dis}	$\overline{\text{OE}}$	B or A	¶	1	6.3	5.7		1	5.5	ns

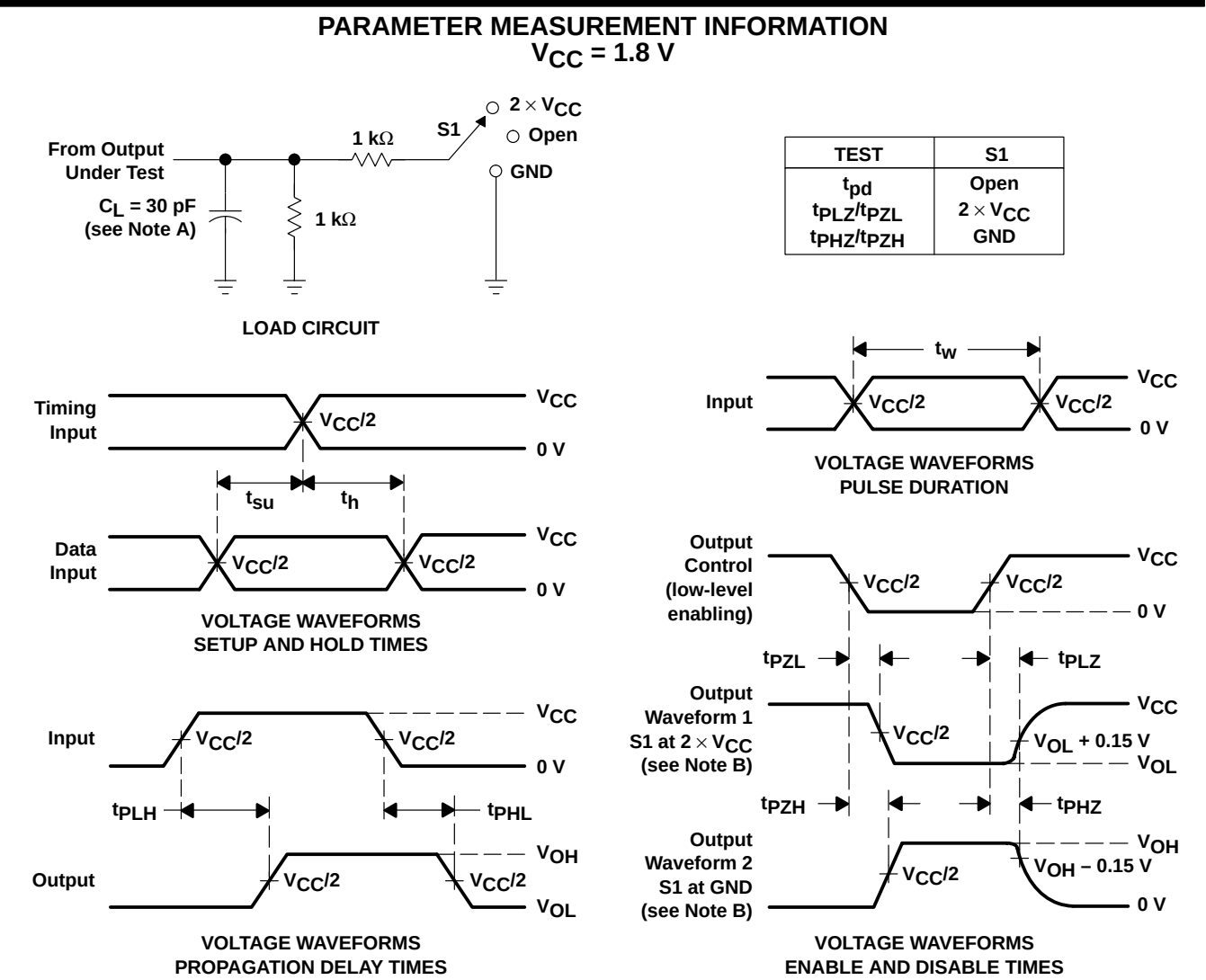
¶ This information was not available at the time of publication.



operating characteristics, $T_A = 25^{\circ}\text{C}$

PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd} Power dissipation capacitance	Outputs enabled	$C_L = 50\text{ pF}, f = 10\text{ MHz}$	†	24	32	pF
	Outputs disabled		†	4	5	

† This information was not available at the time of publication.



Input

V_{CC}

$V_{CC}/2$

0 V

VOLTAGE WAVEFORMS
PULSE DURATION

Output Control (low-level enabling)

V_{CC}

$V_{CC}/2$

0 V

Output Waveform 1
S1 at $2 \times V_{CC}$
(see Note B)

V_{CC}

$V_{CC}/2$

$V_{OL} + 0.15\text{ V}$

V_{OL}

Output Waveform 2
S1 at GND
(see Note B)

V_{OH}

$V_{CC}/2$

$V_{OH} - 0.15\text{ V}$

0 V

VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- A. C_L includes probe and jig capacitance.

B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.

D. The outputs are measured one at a time with one transition per measurement.

E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .

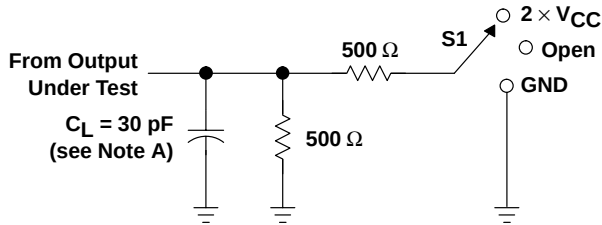
F. t_{PZL} and t_{PZH} are the same as t_{en} .

G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

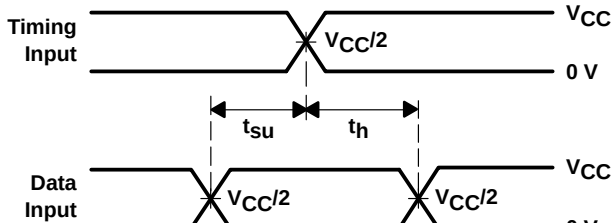
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

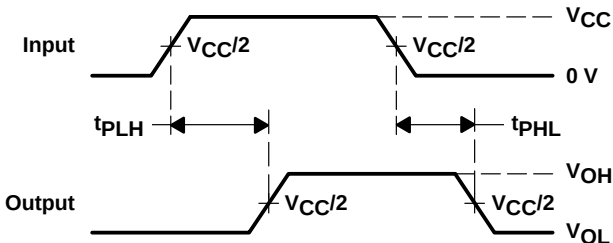


LOAD CIRCUIT

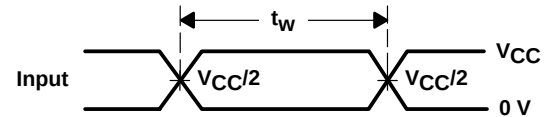
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



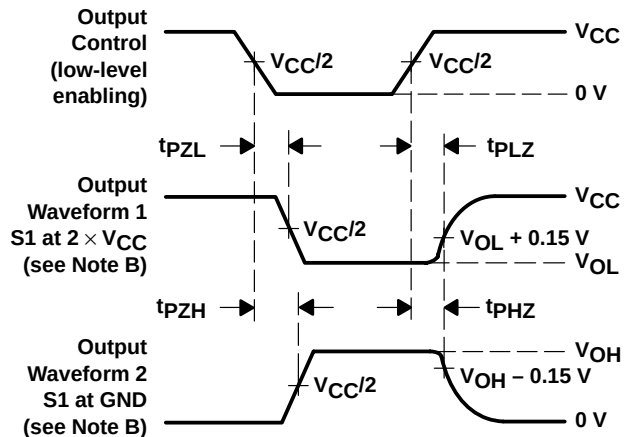
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCHR162245

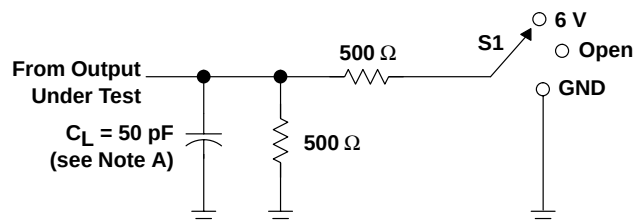
16-BIT BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

SCES064C – DECEMBER 1995 – REVISED FEBRUARY 1999

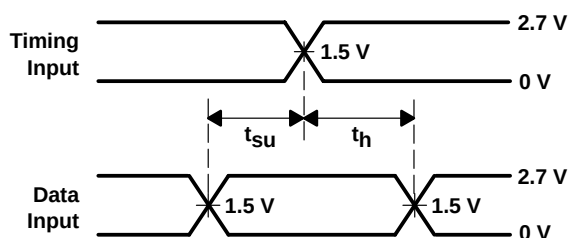
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$

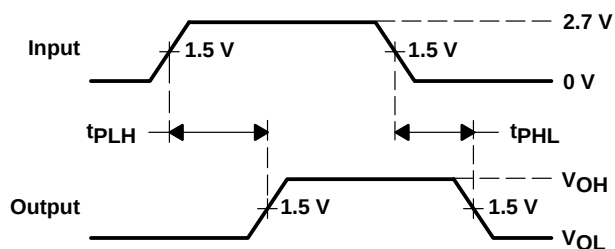


LOAD CIRCUIT

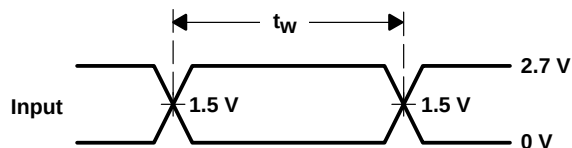
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



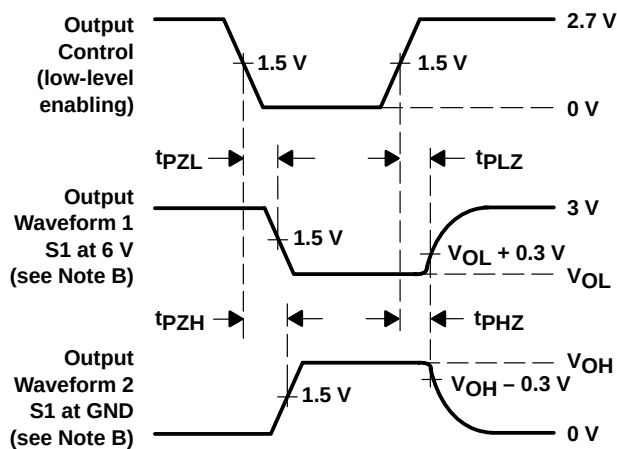
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH162260

12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH

WITH 3-STATE OUTPUTS

SCAS570G – MARCH 1996 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- B-Port Outputs Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Thin-Shrink Small-Outline (DGG) and Plastic Shrink Small-Outline (DL) Packages

description

This 12-bit to 24-bit multiplexed D-type latch is designed for 1.65-V to 3.6-V_{CC} operation.

The SN74ALVCH162260 is used in applications in which two separate data paths must be multiplexed onto, or demultiplexed from, a single data path. Typical applications include multiplexing and/or demultiplexing address and data information in microprocessor or bus-interface applications. This device also is useful in memory-interleaving applications.

Three 12-bit I/O ports (A1–A12, 1B1–1B12, and 2B1–2B12) are available for address and/or data transfer. The output-enable ($\overline{OE1B}$, $\overline{OE2B}$, and $\overline{OEA}$) inputs control the bus transceiver functions. The $\overline{OE1B}$ and $\overline{OE2B}$ control signals also allow bank control in the A-to-B direction.

Address and/or data information can be stored using the internal storage latches. The latch-enable (LE1B, LE2B, LEA1B, and LEA2B) inputs are used to control data storage. When the latch-enable input is high, the latch is transparent. When the latch-enable input goes low, the data present at the inputs is latched and remains latched until the latch-enable input is returned high.

The B outputs, which are designed to sink up to 12 mA, include equivalent 26-Ω resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH162260 is characterized for operation from –40°C to 85°C.

DGG OR DL PACKAGE
(TOP VIEW)

$\overline{OEA}$	1	56	$\overline{OE2B}$
LE1B	2	55	LEA2B
2B3	3	54	2B4
GND	4	53	GND
2B2	5	52	2B5
2B1	6	51	2B6
V _{CC}	7	50	V _{CC}
A1	8	49	2B7
A2	9	48	2B8
A3	10	47	2B9
GND	11	46	GND
A4	12	45	2B10
A5	13	44	2B11
A6	14	43	2B12
A7	15	42	1B12
A8	16	41	1B11
A9	17	40	1B10
GND	18	39	GND
A10	19	38	1B9
A11	20	37	1B8
A12	21	36	1B7
V _{CC}	22	35	V _{CC}
1B1	23	34	1B6
1B2	24	33	1B5
GND	25	32	GND
1B3	26	31	1B4
LE2B	27	30	LEA1B
SEL	28	29	$\overline{OE1B}$

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SN74ALVCH162260
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Function Tables

B TO A
(OEB = H)

INPUTS						OUTPUT A
1B	2B	SEL	LE1B	LE2B	$\overline{OE}A$	
H	X	H	H	X	L	H
L	X	H	H	X	L	L
X	X	H	L	X	L	A ₀
X	H	L	X	H	L	H
X	L	L	X	H	L	L
X	X	L	X	L	L	A ₀
X	X	X	X	X	H	Z

A TO B
(OEA = H)

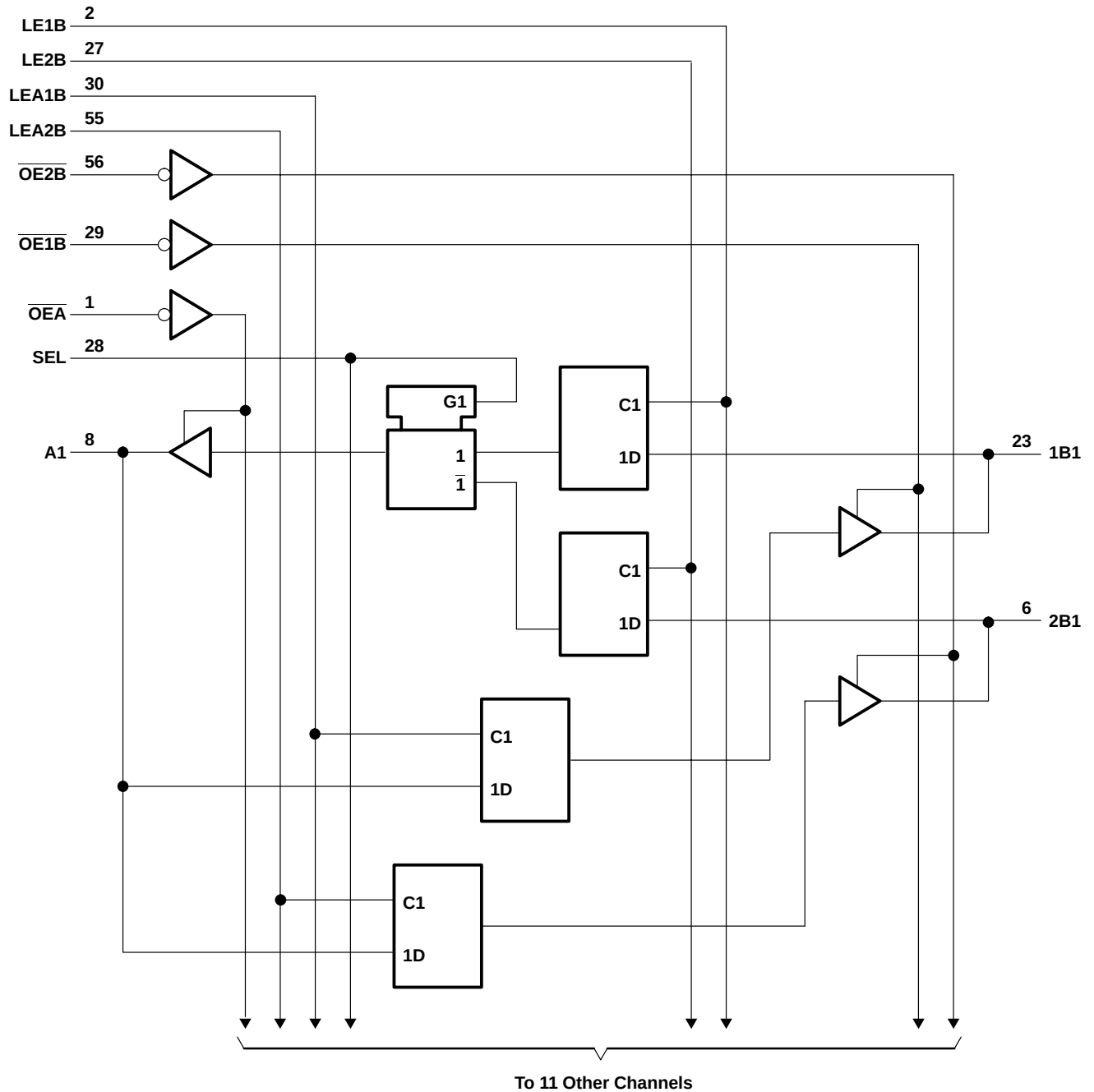
INPUTS					OUTPUTS	
A	LEA1B	LEA2B	$\overline{OE}1B$	$\overline{OE}2B$	1B	2B
H	H	H	L	L	H	H
L	H	H	L	L	L	L
H	H	L	L	L	H	2B ₀
L	H	L	L	L	L	2B ₀
H	L	H	L	L	1B ₀	H
L	L	H	L	L	1B ₀	L
X	L	L	L	L	1B ₀	2B ₀
X	X	X	H	H	Z	Z
X	X	X	L	H	Active	Z
X	X	X	H	L	Z	Active
X	X	X	L	L	Active	Active

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12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH WITH 3-STATE OUTPUTS

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logic diagram (positive logic)



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12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH
WITH 3-STATE OUTPUTS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DGV package	86°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.



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recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current (A port)	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
	High-level output current (B port)	V _{CC} = 1.65 V	−2		
		V _{CC} = 2.3 V	−6		
		V _{CC} = 2.7 V	−8		
		V _{CC} = 3 V	−12		
I _{OL}	Low-level output current (A port)	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
	Low-level output current (B port)	V _{CC} = 1.65 V	2		
		V _{CC} = 2.3 V	6		
		V _{CC} = 2.7 V	8		
		V _{CC} = 3 V	12		
Δt/Δv	Input transition rise or fall rate			10	ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	A port	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
	B port	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}	A port	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
		I _{OL} = 12 mA	2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
	B port	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V		–25			
		V _I = 0.7 V		45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V		75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]		±500			
I _{OZ} [§]		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3.5			pF
C _{iO}	A or B ports	V _O = V _{CC} or GND	3.3 V	4.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		$V_{CC} = 1.8\text{ V}$		$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f_{clock}	Clock frequency	†		150		150		150		MHz
t_w	Pulse duration, LE1B, LE2B, LEA1B, or LEA2B high	†		3.3		3.3		3.3		ns
t_{su}	Setup time, data before LE1B, LE2B, LEA1B, or LEA2B	†		1.4		1.1		1.1		ns
t_h	Hold time, data after LE1B, LE2B, LEA1B, or LEA2B	†		1.6		1.9		1.5		ns

† This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 1.8\text{ V}$		$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f_{max}			†		150		150		150		MHz
t_{pd}	A	B	†		1	5.9	5.8		1.2	4.9	ns
	B	A	†		1	5.7	5.1		1.2	4.3	
	LE	A	†		1	5.6	5.2		1	4.4	
		B	†		1	6.1	5.9		1	5	
	SEL	A	†		1	6.9	6.6		1.1	5.6	
t_{en}	$\overline{\text{OE}}$	A	†		1	6.7	6.4		1	5.4	ns
		B	†		1	7.2	7.1		1	6	
t_{dis}	$\overline{\text{OE}}$	A	†		1	5.7	5		1.3	4.6	ns
		B	†		1	6.2	5.5		1.3	5.1	

† This information was not available at the time of publication.

operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER			TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
				TYP	TYP	TYP	
C_{pd}	Power dissipation capacitance	All outputs enabled	$C_L = 50\text{ pF}, f = 10\text{ MHz}$	†	37	41	pF
		All outputs disabled		†	4	7	

† This information was not available at the time of publication.

SN74ALVCH162260

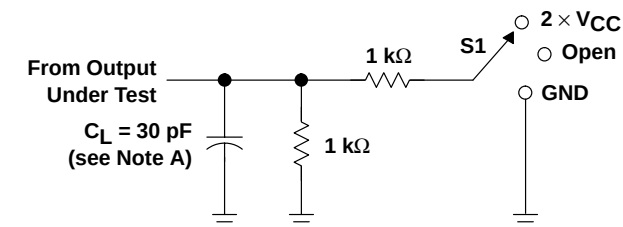
12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH

WITH 3-STATE OUTPUTS

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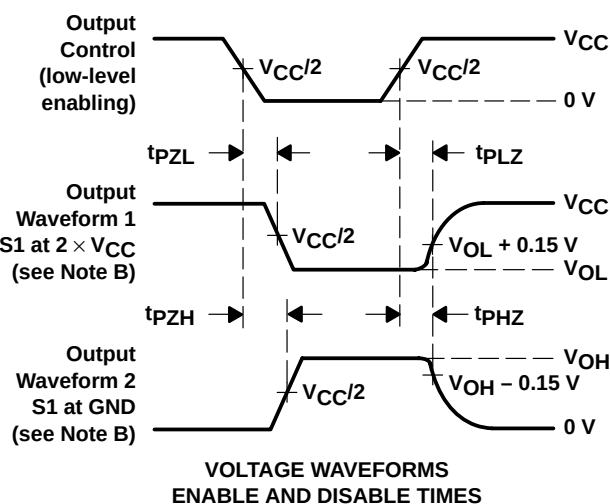
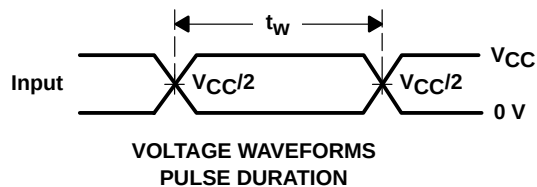
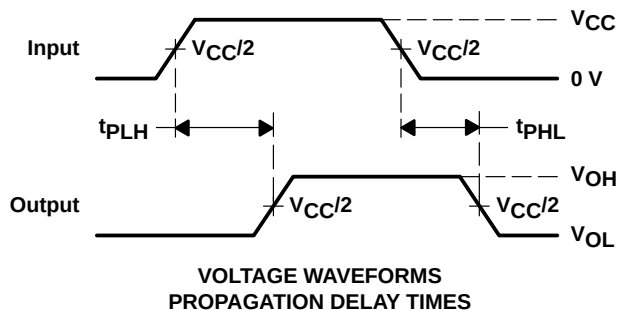
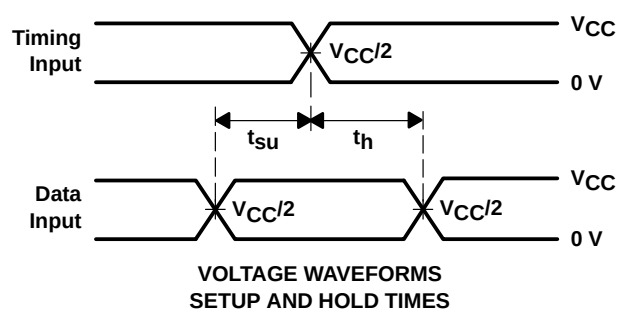
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PHZ}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

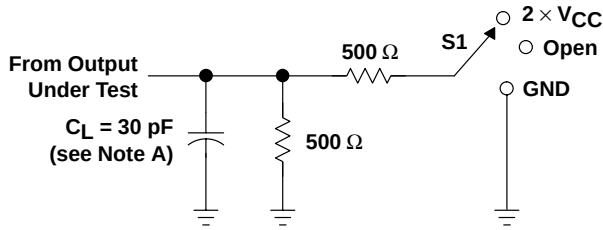
SN74ALVCH162260

12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH WITH 3-STATE OUTPUTS

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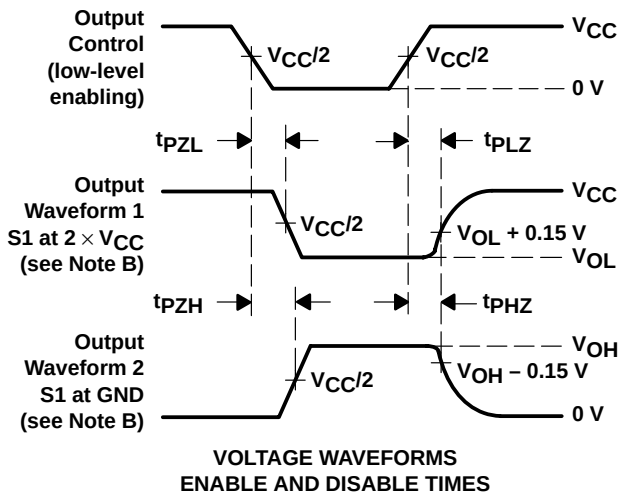
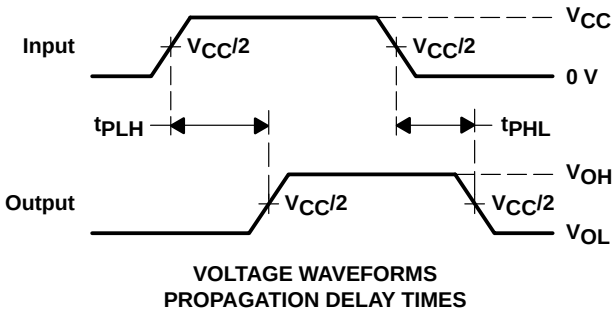
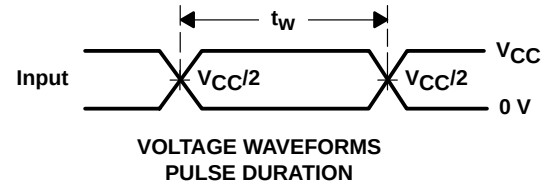
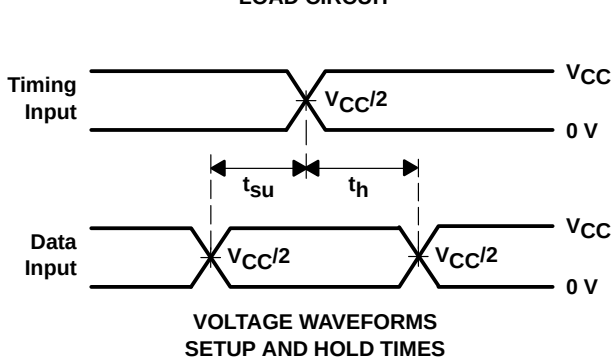
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH162260

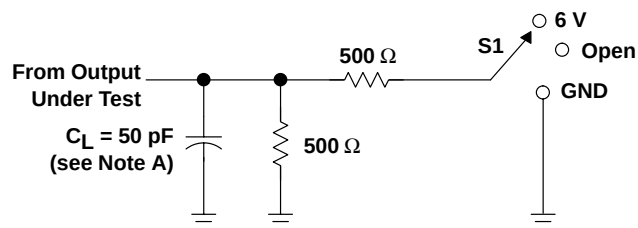
12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH

WITH 3-STATE OUTPUTS

SCAS570G – MARCH 1996 – REVISED FEBRUARY 1999

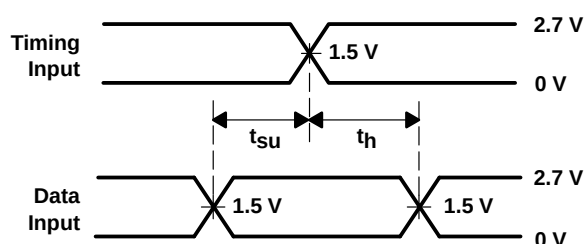
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

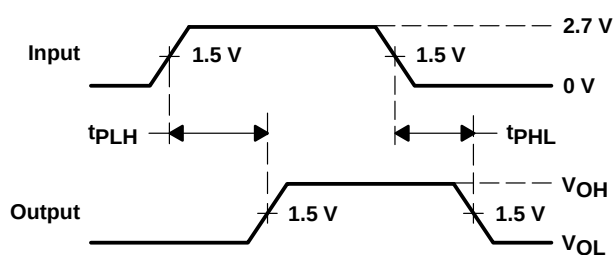


LOAD CIRCUIT

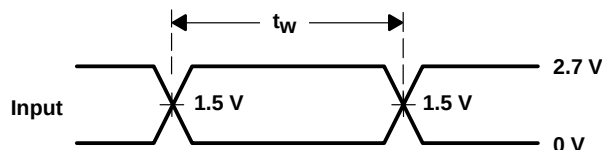
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



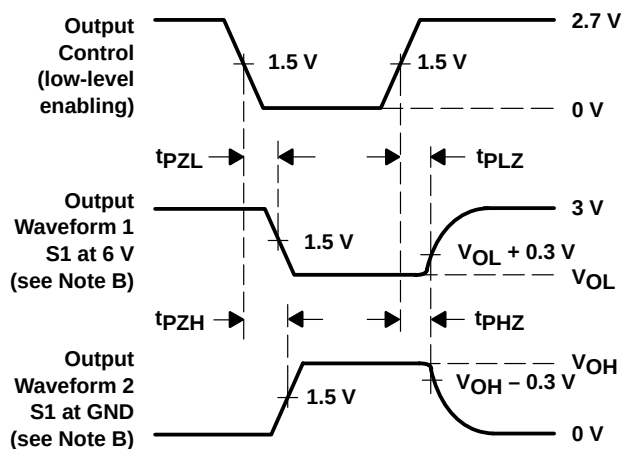
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH162268

12-BIT TO 24-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

SCES018F – AUGUST 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- B-Port Outputs Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 12-bit to 24-bit registered bus exchanger is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH162268 is used for applications in which data must be transferred from a narrow high-speed bus to a wide, lower-frequency bus.

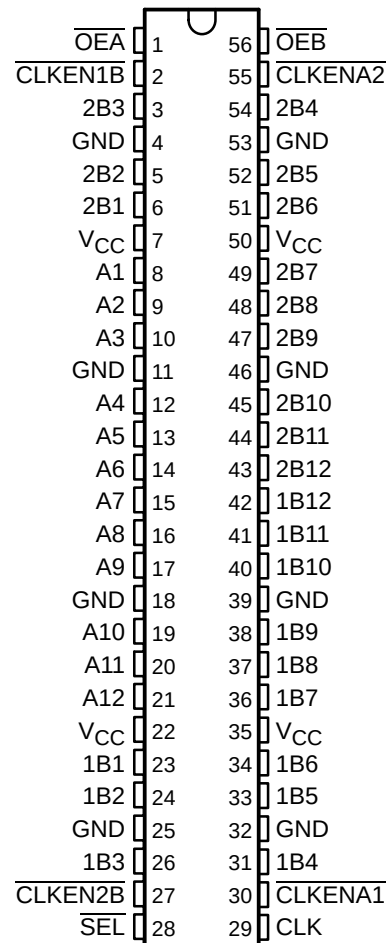
The device provides synchronous data exchange between the two ports. Data is stored in the internal registers on the low-to-high transition of the clock (CLK) input when the appropriate clock-enable ($\overline{CLKEN}$) inputs are low. The select ($\overline{SEL}$) line is synchronous with CLK and selects 1B or 2B input data for the A outputs.

For data transfer in the A-to-B direction, a two-stage pipeline is provided in the A-to-1B path, with a single storage register in the A-to-2B path. Proper control of these inputs allows two sequential 12-bit words to be presented synchronously as a 24-bit word on the B port. Data flow is controlled by the active-low output enables ($\overline{OEA}$, $\overline{OEB}$). These control terminals are registered so bus direction changes are synchronous with CLK.

The B outputs, which are designed to sink up to 12 mA, include equivalent 26-Ω resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, a clock pulse should be applied as soon as possible and $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver. Due to $\overline{OE}$ being routed through a register, the active state of the outputs cannot be determined prior to the arrival of the first clock pulse.

DGG OR DL PACKAGE
(TOP VIEW)



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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SN74ALVCH162268
12-BIT TO 24-BIT REGISTERED BUS EXCHANGER
WITH 3-STATE OUTPUTS

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description (continued)

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH162268 is characterized for operation from –40°C to 85°C.

Function Tables

OUTPUT ENABLE

INPUTS			OUTPUTS	
CLK	OEA	OEB	A	1B, 2B
↑	H	H	Z	Z
↑	H	L	Z	Active
↑	L	H	Active	Z
↑	L	L	Active	Active

A-TO-B STORAGE
(OEB = L)

INPUTS				OUTPUTS	
CLKENA1	CLKENA2	CLK	A	1B	2B
H	H	X	X	1B ₀ [†]	2B ₀ [†]
L	L	↑	L	L [†]	X
L	L	↑	H	H [†]	X
X	L	↑	L	X	L
X	L	↑	H	X	H

† Two CLK edges are needed to propagate data.

‡ Output level before the indicated steady-state input conditions were established

B-TO-A STORAGE
(OEA = L)

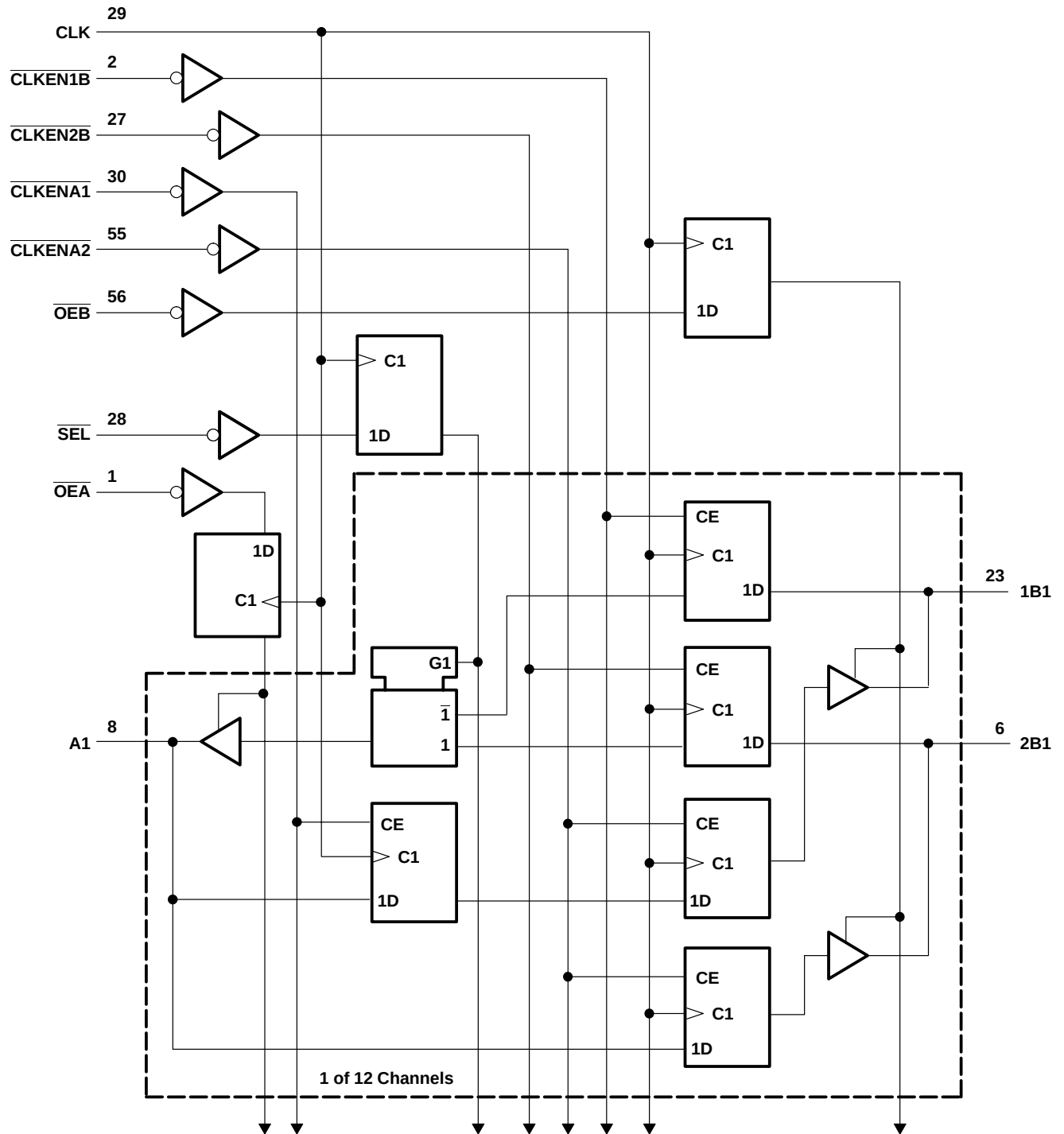
INPUTS						OUTPUT A
CLKEN1B	CLKEN2B	CLK	SEL	1B	2B	
H	X	X	H	X	X	A ₀ [‡]
X	H	X	L	X	X	A ₀ [‡]
L	L	↑	H	L	X	L
L	L	↑	H	H	X	H
X	L	↑	L	X	L	L
X	L	↑	L	X	H	H

‡ Output level before the indicated steady-state input conditions were established

SN74ALVCH162268
12-BIT TO 24-BIT REGISTERED BUS EXCHANGER
WITH 3-STATE OUTPUTS

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logic diagram (positive logic)



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12-BIT TO 24-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.



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12-BIT TO 24-BIT REGISTERED BUS EXCHANGER
WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current (A port)	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
	High-level output current (B port)	V _{CC} = 1.65 V	−2		
		V _{CC} = 2.3 V	−6		
		V _{CC} = 2.7 V	−8		
		V _{CC} = 3 V	−12		
I _{OL}	Low-level output current (A port)	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
	Low-level output current (B port)	V _{CC} = 1.65 V	2		
		V _{CC} = 2.3 V	6		
		V _{CC} = 2.7 V	8		
		V _{CC} = 3 V	12		
Δt/Δv	Input transition rise or fall rate			10	ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

SN74ALVCH162268
12-BIT TO 24-BIT REGISTERED BUS EXCHANGER
WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	A port	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
	B port	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}	A port	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
		I _{OL} = 12 mA	2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
	B port	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V		–25			
		V _I = 0.7 V		45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V		75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]		±500			
I _{OZ} [§]		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3.5			pF
C _{iO}	A or B ports	V _O = V _{CC} or GND	3.3 V	9			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.



SN74ALVCH162268
12-BIT TO 24-BIT REGISTERED BUS EXCHANGER
WITH 3-STATE OUTPUTS

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency	†		120		125		150		MHz
t _w	Pulse duration, CLK high or low	†		3.3		3.3		3.3		ns
t _{su}	Setup time	A data before CLK↑		†		4.5		4		ns
		B data before CLK↑		†		0.8		1.2		
		SEL before CLK↑		†		1.4		1.6		
		CLKENA1 or CLKENA2 before CLK↑		†		3.6		3.4		
		CLKENB1 or CLKENB2 before CLK↑		†		3.2		3		
		OE before CLK↑		†		4.2		3.9		
t _h	Hold time	A data after CLK↑		†		0		0		ns
		B data after CLK↑		†		1.3		1.2		
		SEL after CLK↑		†		1		1		
		CLKENA1 or CLKENA2 after CLK↑		†		0.1		0.1		
		CLKENB1 or CLKENB2 after CLK↑		†		0.1		0		
		OE after CLK↑ after CLK↑		†		0		0		

† This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 1.8\text{ V}$		$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f_{max}			†		120		125		150		MHz
t_{pd}	CLK	B	†		1.6	6.1	5.9		1.8	5.4	ns
		A (1B)	†		1.6	5.8	5.4		1.7	4.8	
		A (2B)	†		1.6	5.8	5.3		1.8	4.8	
		A (SEL)	†		2.5	7.3	6.5		2.4	5.8	
t_{en}	CLK	B	†		2.7	7.2	6.8		2.6	6.1	ns
t_{dis}	CLK	B	†		2.8	7.2	6.1		2.5	5.9	ns
t_{en}	CLK	A	†		2	6.2	5.6		1.8	5.1	ns
t_{dis}	CLK	A	†		2	6.5	5.4		2.1	5	ns

† This information was not available at the time of publication.

operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER			TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
				TYP	TYP	TYP	
C_{pd}	Power dissipation capacitance	Outputs enabled	$C_L = 50\text{ pF}, f = 10\text{ MHz}$	†	87	120	pF
		Outputs disabled		†	80.5	118	

† This information was not available at the time of publication.

SN74ALVCH162268

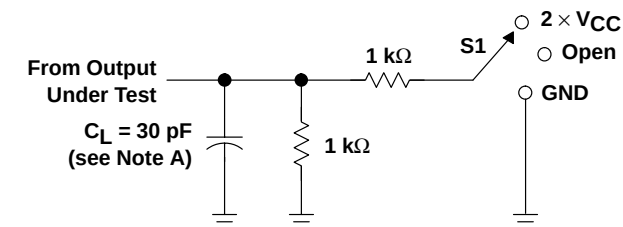
12-BIT TO 24-BIT REGISTERED BUS EXCHANGER

WITH 3-STATE OUTPUTS

SCES018F – AUGUST 1995 – REVISED FEBRUARY 1999

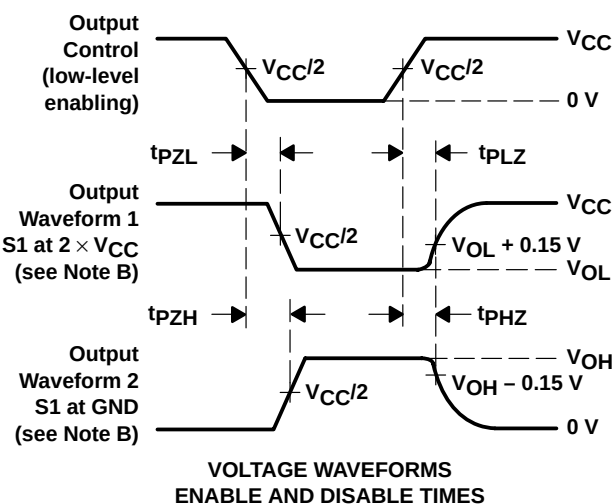
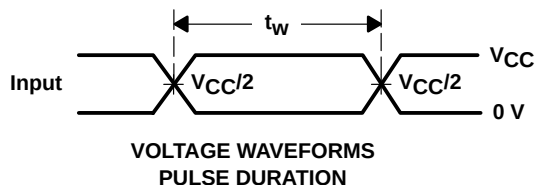
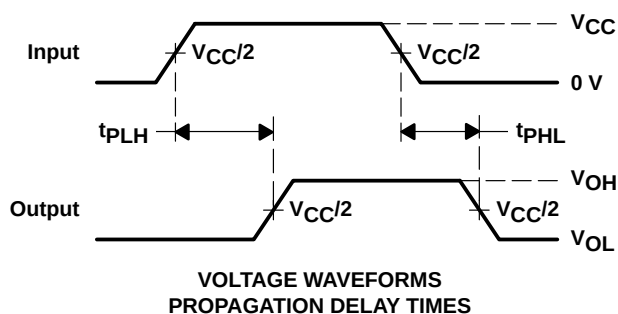
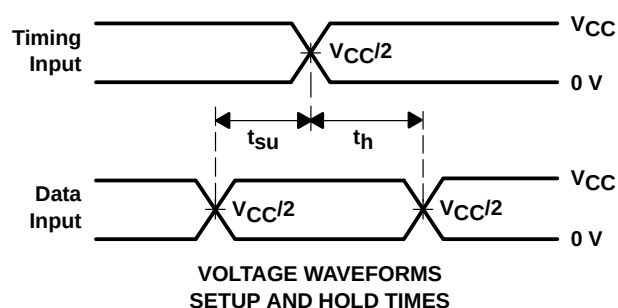
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PHL}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

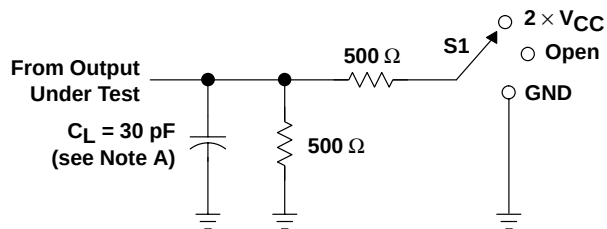
SN74ALVCH162268

12-BIT TO 24-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

SCES018F – AUGUST 1995 – REVISED FEBRUARY 1999

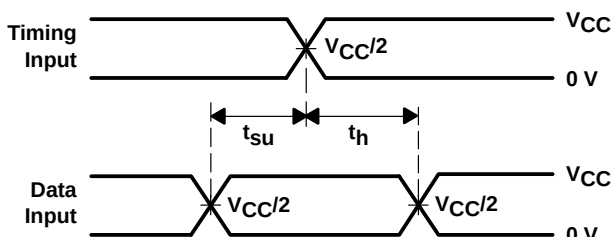
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

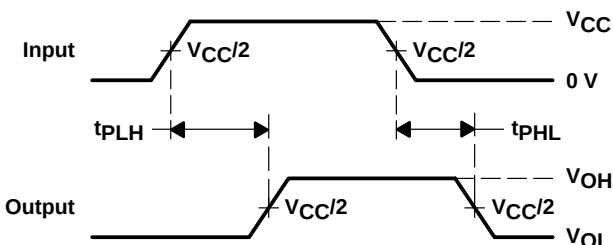


LOAD CIRCUIT

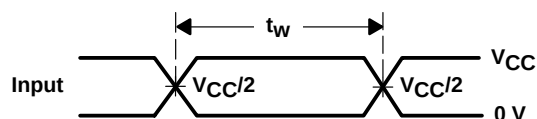
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



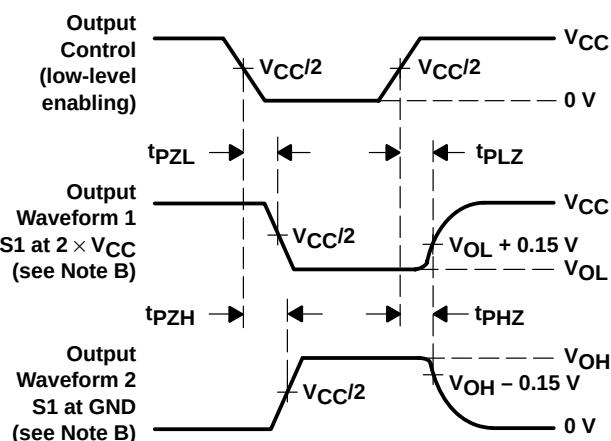
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH162268

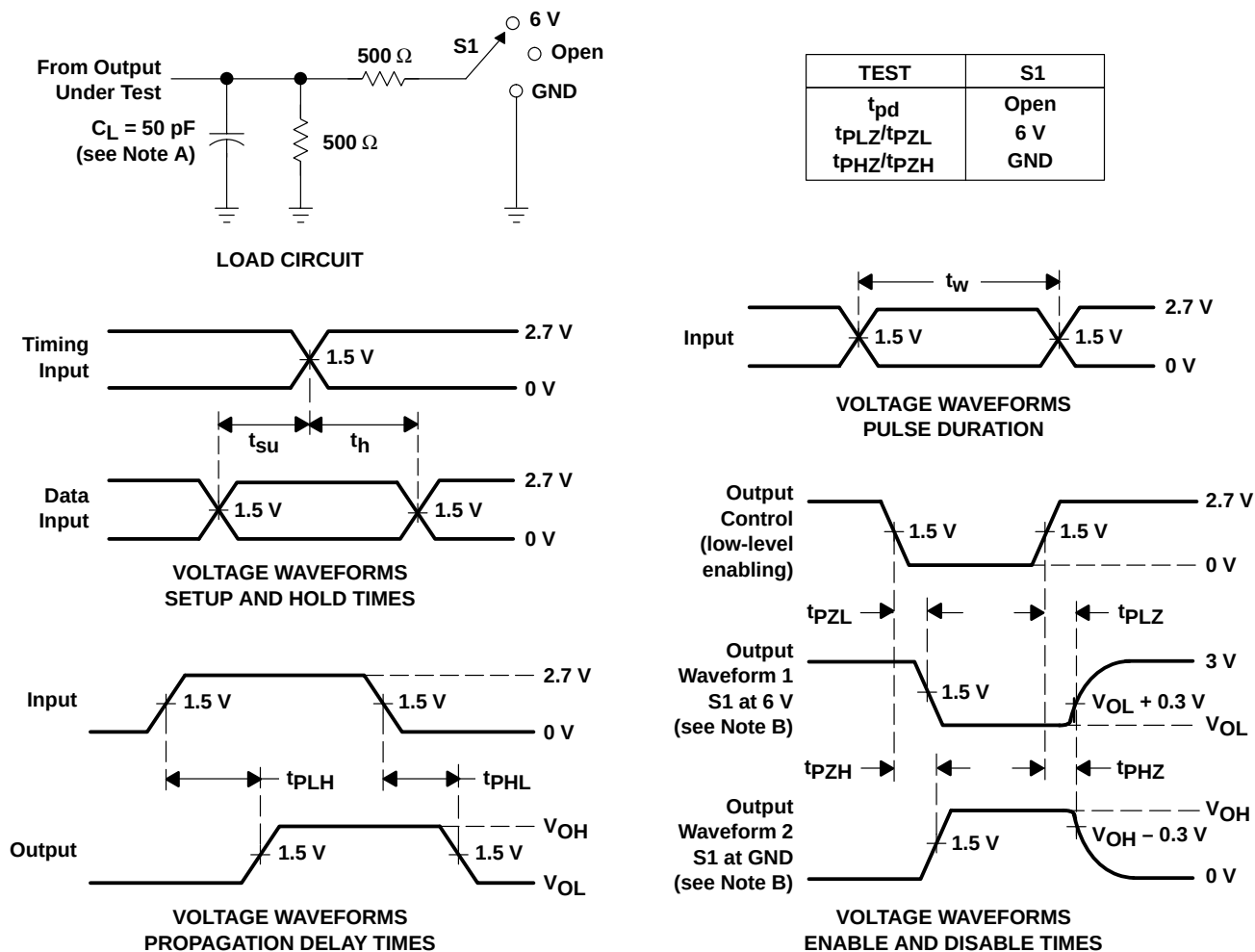
12-BIT TO 24-BIT REGISTERED BUS EXCHANGER

WITH 3-STATE OUTPUTS

SCES018F – AUGUST 1995 – REVISED FEBRUARY 1999

PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCHR162282

18-BIT TO 36-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

SCES087A – SEPTEMBER 1996 – REVISED FEBRUARY 1999

- **EPIC™ (Enhanced-Performance Implanted CMOS) Sub-Micron Process**
- **Output Ports Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required**
- **Member of the Texas Instruments Widebus™ Family**
- **Bus-Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors**
- **Packaged in Thin Shrink Small-Outline Package**

NOTE: For order entry:
The DBB package is abbreviated to G.

description

The SN74ALVCHR162282 is an 18-bit to 36-bit registered bus exchanger designed for 1.65-V to 3.6-V V_{CC} operation.

This part is intended for use in applications where data must be transferred from a narrow high-speed bus to a wide lower-frequency bus. It is designed specifically for low-voltage (3.3-V) V_{CC} operation.

The device provides synchronous data exchange between the two ports. Data is stored in the internal registers on the low-to-high transition of the clock (CLK) input. For data transfer in the B-to-A direction, select ($\overline{SEL}$) line selects 1B or 2B data for the A outputs.

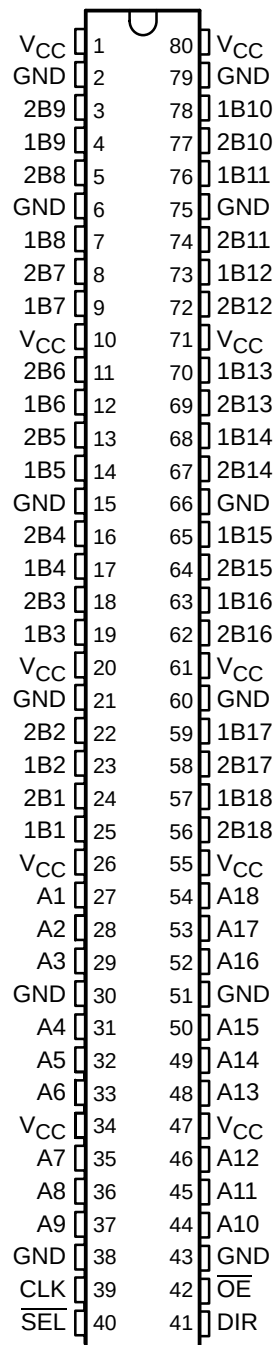
For data transfer in the A-to-B direction, a two-stage pipeline is provided in the 1B path, with a single storage register in the 2B path. Data flow is controlled by the active-low output enable ($\overline{OE}$) and the control (DIR) input. The DIR control pin is registered to synchronize the bus direction changes with the clock.

The outputs, which are designed to sink up to 12mA, include 26-Ω resistors to reduce overshoot and undershoot.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCHR162282 is characterized for operation from -40°C to 85°C.

DBB PACKAGE
(TOP VIEW)



PRODUCT PREVIEW

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SN74ALVCHR162282
18-BIT TO 36-BIT REGISTERED BUS EXCHANGER
WITH 3-STATE OUTPUTS

SCES087A – SEPTEMBER 1996 – REVISED FEBRUARY 1999

Function Tables

A-TO-B STORAGE
($\overline{OE} = L$, $DIR = H$)

INPUTS			OUTPUTS	
SEL	CLK	A	1B	2B
H	X	X	1B ₀ [†]	2B ₀ [†]
L	↑	L	L [‡]	X
L	↑	H	H [‡]	X

[†] Output level before the indicated steady-state input conditions are established

[‡] Two CLK edges are needed to propagate the data.

B-TO-A STORAGE
($\overline{OE} = L$, $DIR = L$)

INPUTS				OUTPUT A
CLK	SEL	1B	2B	
↑	H	X	L	L [§]
↑	H	X	H	H [§]
↑	L	L	X	L
↑	L	H	X	H

[§] Two clock edges are needed to propagate the data. The data is loaded in the first register when $\overline{SEL}$ is low and propagates to the second register when $\overline{SEL}$ is high.

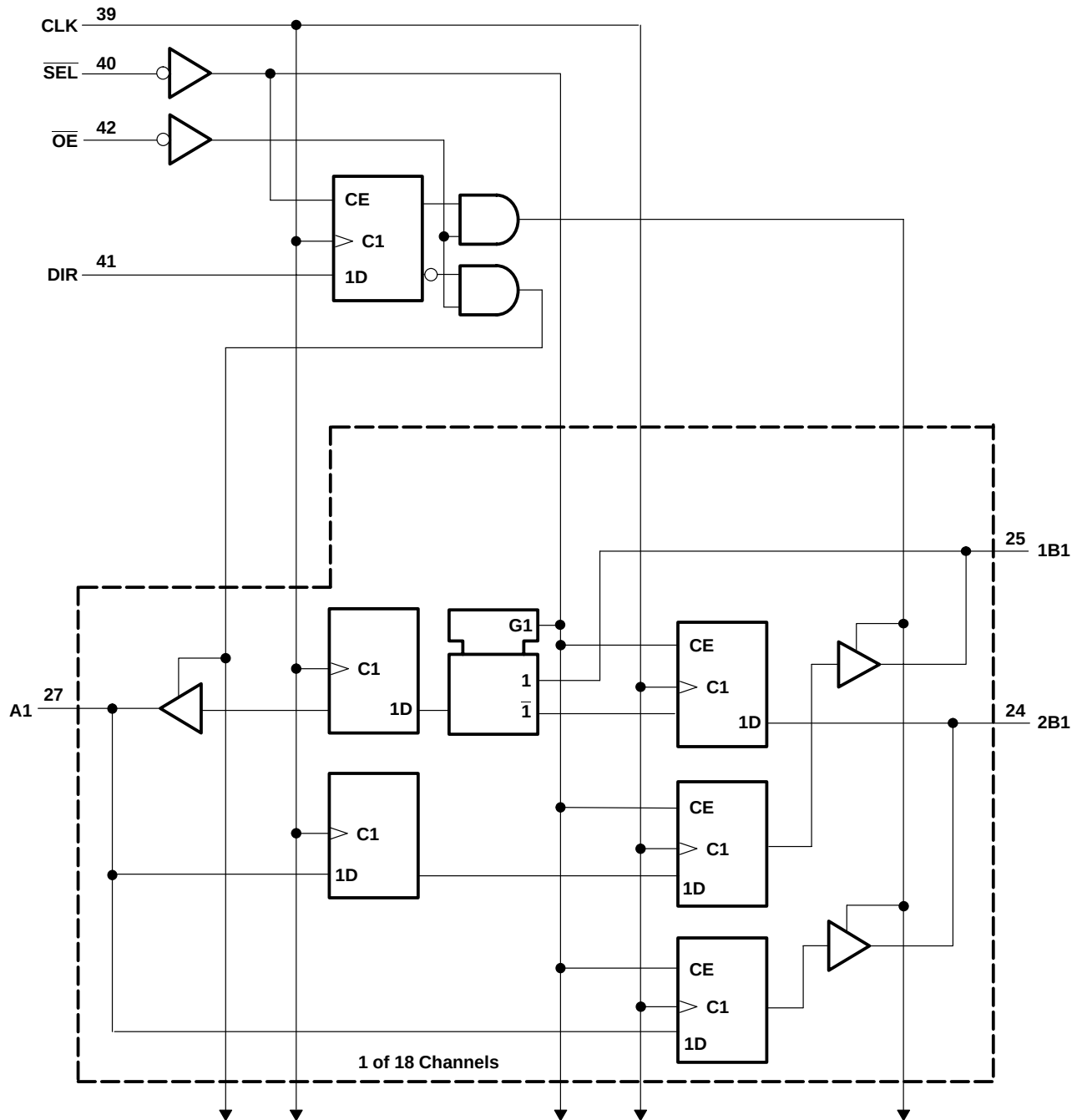
OUTPUT ENABLE

INPUTS			OUTPUTS	
CLK	$\overline{OE}$	DIR	A	1B, 2B
↑	H	X	Z	Z
↑	L	L	Z	Active
↑	L	H	Active	Z

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logic diagram (positive logic)



PRODUCT PREVIEW



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Maximum power dissipation at $T_A = 55^\circ\text{C}$ (in still air) (see Note 3)	0.84 W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils. For more information, refer to the *Package Thermal Considerations* application note in the *ABT Advanced BiCMOS Technology Data Book*.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–2	mA
		$V_{CC} = 2.3$ V	–6	
		$V_{CC} = 2.7$ V	–8	
		$V_{CC} = 3$ V	–12	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	2	mA
		$V_{CC} = 2.3$ V	6	
		$V_{CC} = 2.7$ V	8	
		$V_{CC} = 3$ V	12	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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18-BIT TO 36-BIT REGISTERED BUS EXCHANGER
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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V			±5	µA
I _I (hold)		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V		–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V		–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V		–75			
		V _I = 0 to 3.6 V [‡]	3.6 V			±500	
I _{OZ} [§]		V _O = V _{CC} or GND	3.6 V			±10	µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V			40	µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V			750	µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V				pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V				pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.

PRODUCT PREVIEW



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18-BIT TO 36-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT	
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
f _{clock}	Clock frequency										MHz
t _w	Pulse duration, CLK high or low										ns
t _{su}	Setup time	A data before CLK↑									ns
		B data before CLK↑									
		DIR before CLK↑									
		$\overline{\text{SEL}}$ before CLK↑									
t _h	Hold time	A data after CLK↑									ns
		B data after CLK↑									
		DIR after CLK↑									
		$\overline{\text{SEL}}$ after CLK↑									

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}											MHz
t _{pd}	CLK	A									ns
	CLK	B									
t _{en}	$\overline{\text{OE}}$	A									ns
	$\overline{\text{OE}}$	B									
t _{dis}	$\overline{\text{OE}}$	A									ns
	$\overline{\text{OE}}$	B									

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 0, f = 10 MHz				pF
		Outputs disabled					

PRODUCT PREVIEW



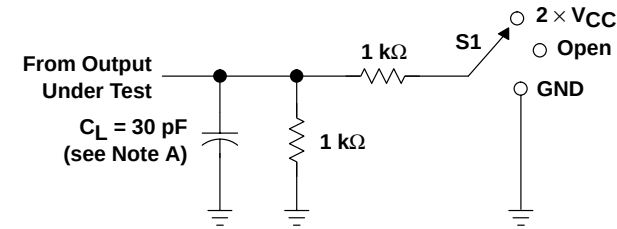
SN74ALVCHR162282

18-BIT TO 36-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

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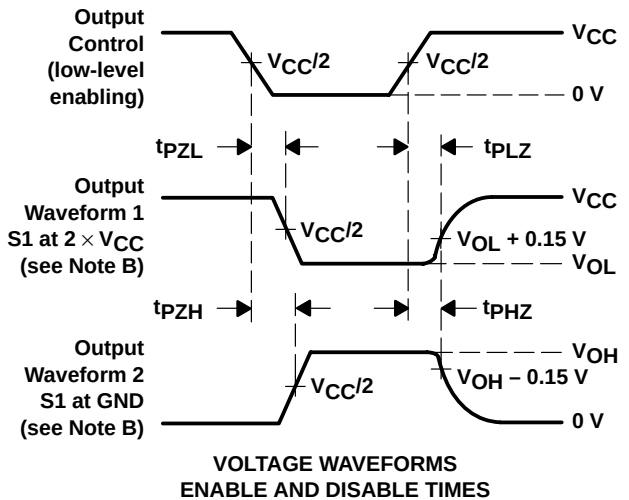
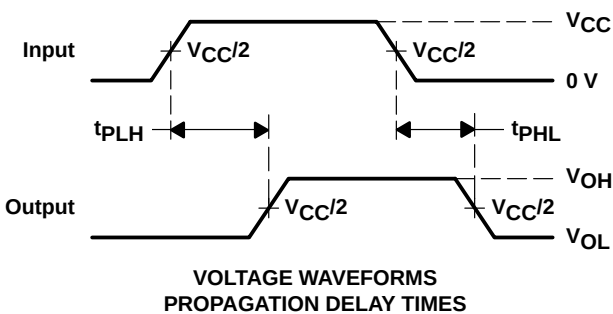
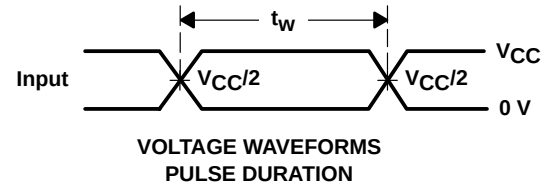
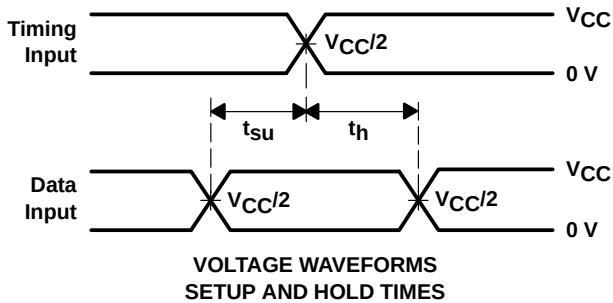
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

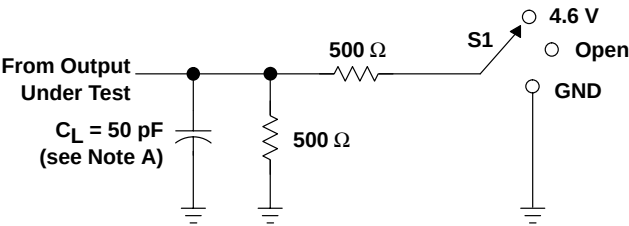
Figure 1. Load Circuit and Voltage Waveforms

PRODUCT PREVIEW

SN74ALVCHR162282
18-BIT TO 36-BIT REGISTERED BUS EXCHANGER
WITH 3-STATE OUTPUTS

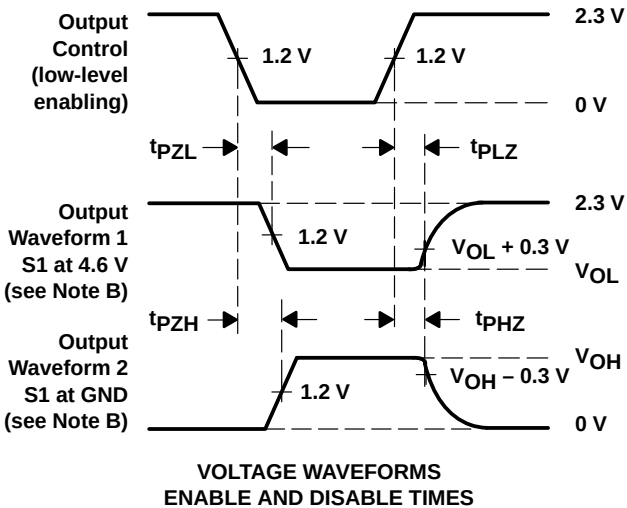
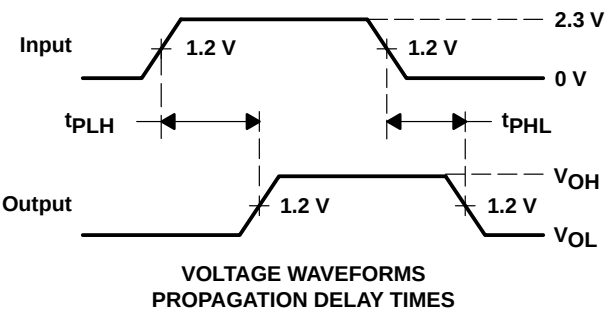
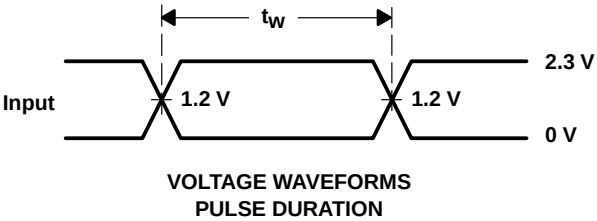
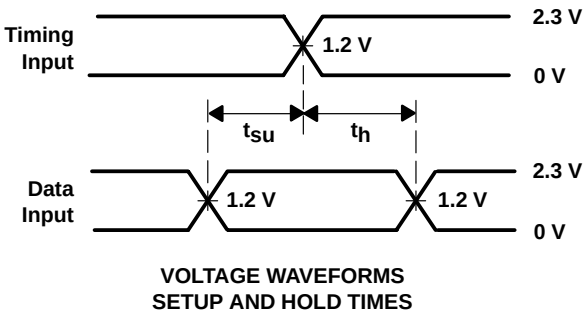
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PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$



TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	4.6 V
t_{PHZ}/t_{PHL}	GND

LOAD CIRCUIT



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

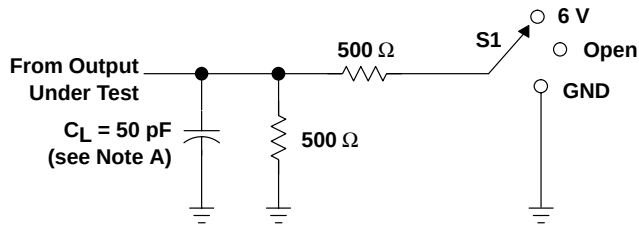
SN74ALVCHR162282

18-BIT TO 36-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

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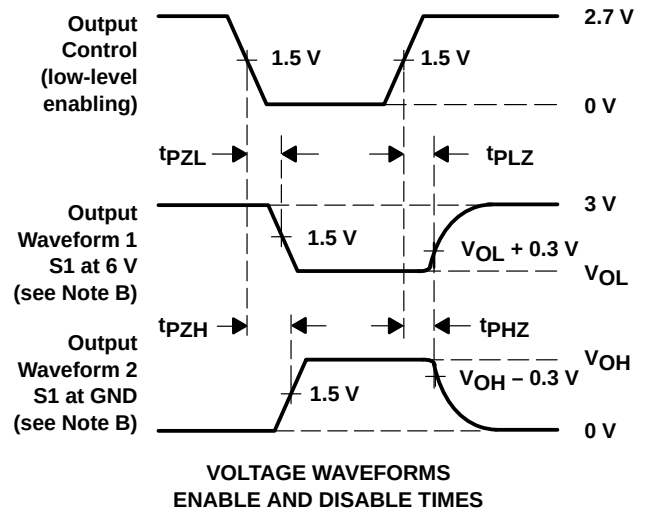
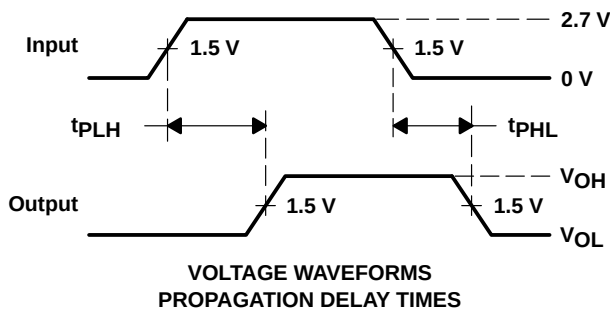
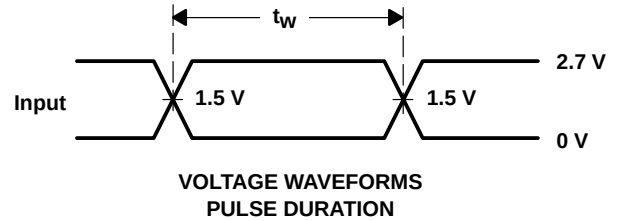
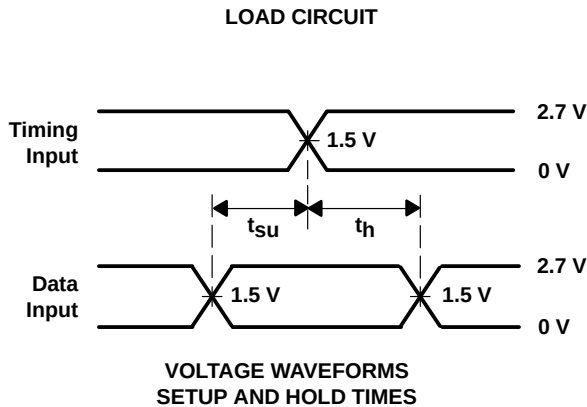
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V}$ AND $3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PHL}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

PRODUCT PREVIEW

SN74ALVC162334

16-BIT UNIVERSAL BUS DRIVER WITH 3-STATE OUTPUTS

SCES127C – FEBRUARY 1998 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- Ideal for Use in PC100 Register DIMM
- Output Ports Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- Designed to Comply With JEDEC 168-Pin and 200-Pin SDRAM Buffered DIMM Specification
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Package Options Include Plastic Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages

description

This 16-bit universal bus driver is designed for 1.65-V to 3.6-V V_{CC} operation.

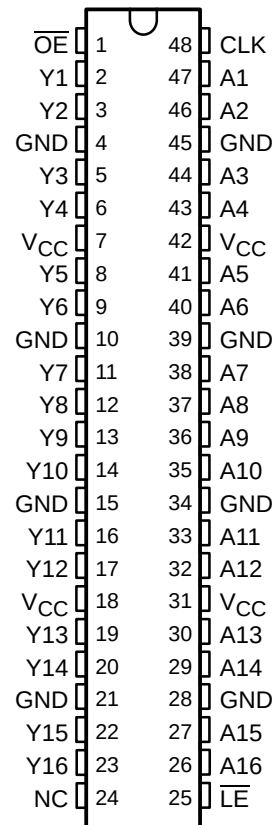
Data flow from A to Y is controlled by the output-enable ($\overline{OE}$) input. The device operates in the transparent mode when the latch-enable ($\overline{LE}$) input is low. When $\overline{LE}$ is high, the A data is latched if the clock (CLK) input is held at a high or low logic level. If $\overline{LE}$ is high, the A data is stored in the latch/flip-flop on the low-to-high transition of CLK. When $\overline{OE}$ is high, the outputs are in the high-impedance state.

The outputs, which are designed to sink up to 12 mA, include equivalent 26-Ω resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74ALVC162334 is characterized for operation from –40°C to 85°C.

DGG, DGV, OR DL PACKAGE
(TOP VIEW)



NC – No internal connection

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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SN74ALVC162334

16-BIT UNIVERSAL BUS DRIVER

WITH 3-STATE OUTPUTS

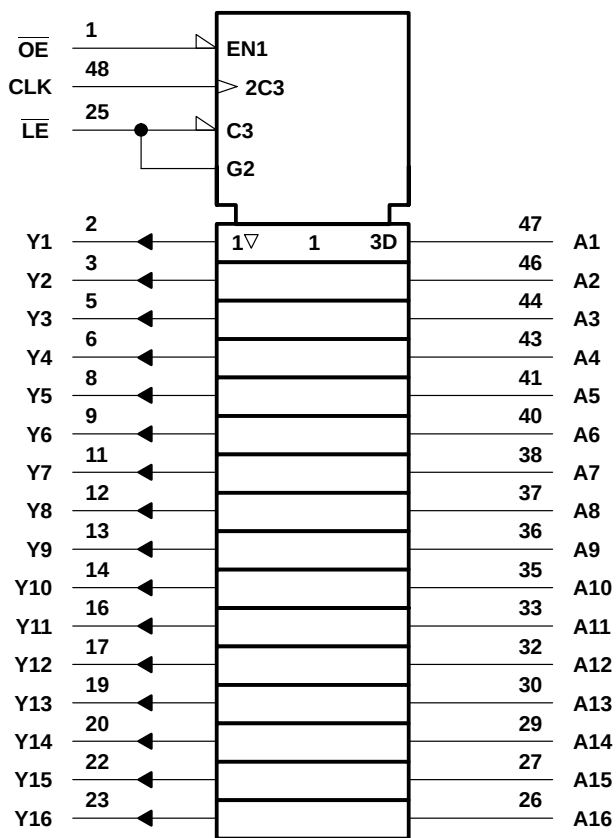
SCES127C – FEBRUARY 1998 – REVISED FEBRUARY 1999

FUNCTION TABLE

INPUTS				OUTPUT Y
OE	LE	CLK	A	
H	X	X	X	Z
L	L	X	L	L
L	L	X	H	H
L	H	↑	L	L
L	H	↑	H	H
L	H	L or H	X	$Y_0^{\dagger}$

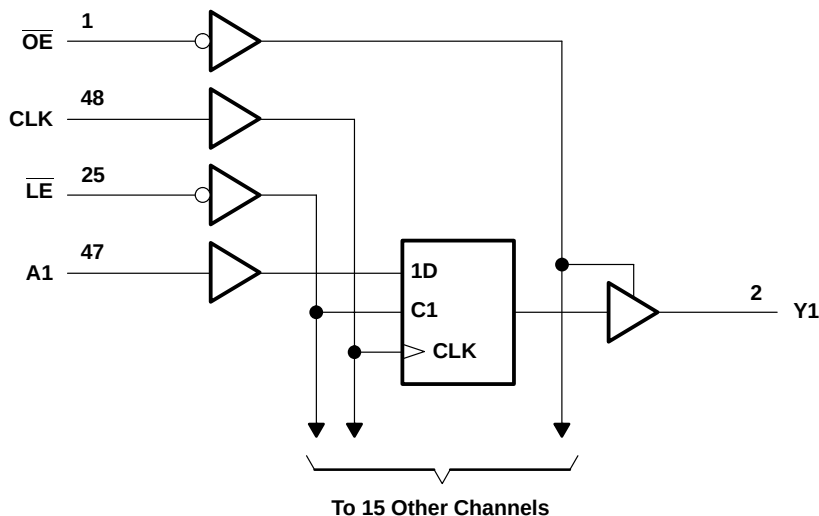
[†] Output level before the indicated steady-state input conditions were established

logic symbol[‡]



‡ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3):	
DGG package	89°C/W
DGV package	93°C/W
DL package	94°C/W
Storage temperature range, T_{Stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

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16-BIT UNIVERSAL BUS DRIVER
WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–2	mA
		$V_{CC} = 2.3 \text{ V}$	–6	
		$V_{CC} = 2.7 \text{ V}$	–8	
		$V_{CC} = 3 \text{ V}$	–12	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	2	mA
		$V_{CC} = 2.3 \text{ V}$	6	
		$V_{CC} = 2.7 \text{ V}$	8	
		$V_{CC} = 3 \text{ V}$	12	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

SN74ALVC162334
16-BIT UNIVERSAL BUS DRIVER
WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	5			pF
	Data inputs			5.5			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT	
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
f _{clock}	Clock frequency		‡		150		150		150		MHz	
t _w	Pulse duration	LE low	‡		3.3		3.3		3.3		ns	
		CLK high or low		‡		3.3		3.3				
t _{su}	Setup time	Data before CLK↑		‡		1.4		1.7		1.5		ns
		Data before LE↑	CLK high	‡		1.2		1.6		1.3		
			CLK low	‡		1.4		1.5		1.2		
t _h	Hold time	Data after CLK↑		‡		0.9		0.9		0.9		ns
		Data after LE↑	CLK high or low	‡		1.1		1.1		1.1		

‡ This information was not available at the time of publication.



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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	A	Y	†		1	4.4	4.5		1.1	3.9	ns
	$\overline{LE}$		†		1	5.8	6		1.3	5	
	CLK		†		1	5.2	5.4		1	4.9	
t _{en}	$\overline{OE}$	Y	†		1	6.4	6.4		1.1	5.4	ns
t _{dis}	$\overline{OE}$	Y	†		1	4.7	5.1		1.7	5	ns

† This information was not available at the time of publication.

switching characteristics from 0°C to 65°C, C_L = 50 pF

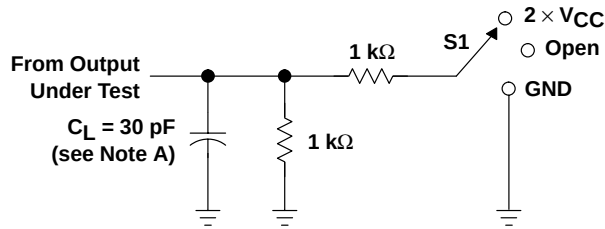
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 3.3 V ± 0.15 V		UNIT
			MIN	MAX	
t _{pd}	A	Y	1.2	3.8	ns
	CLK	Y	1.1	4.8	

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 0, f = 10 MHz	†	31	36	pF
		Outputs disabled		†	7	11	

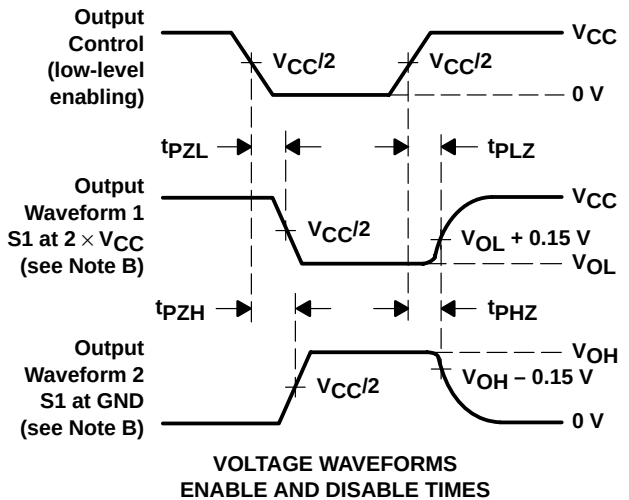
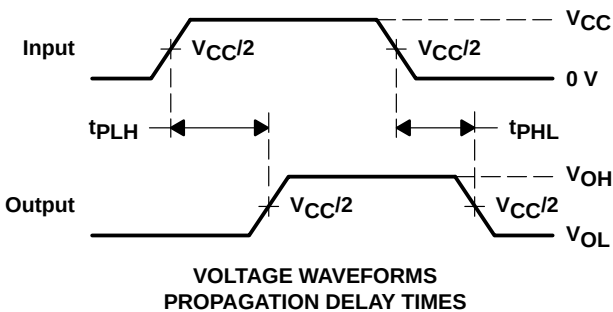
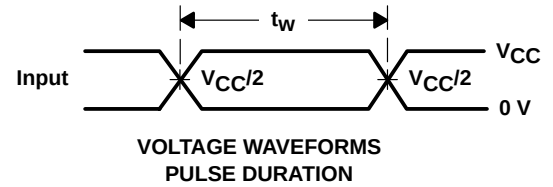
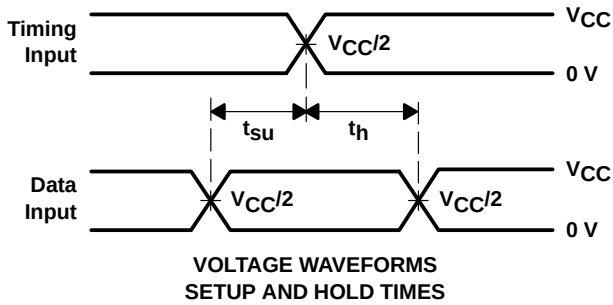
† This information was not available at the time of publication.

PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVC162334

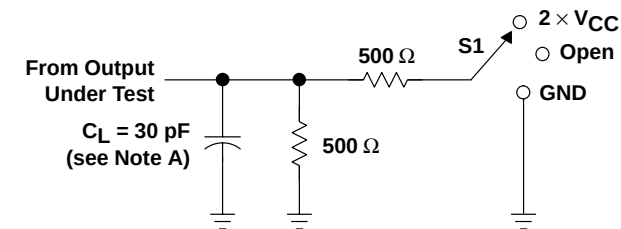
16-BIT UNIVERSAL BUS DRIVER

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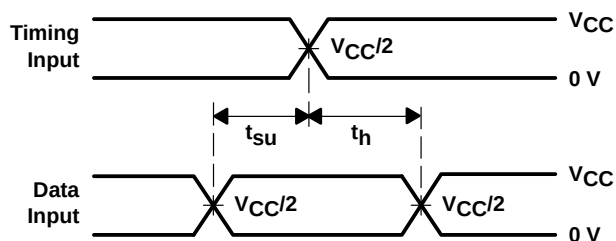
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

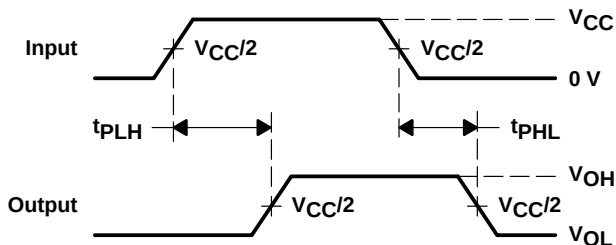


LOAD CIRCUIT

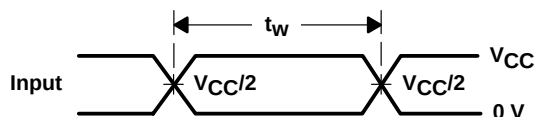
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



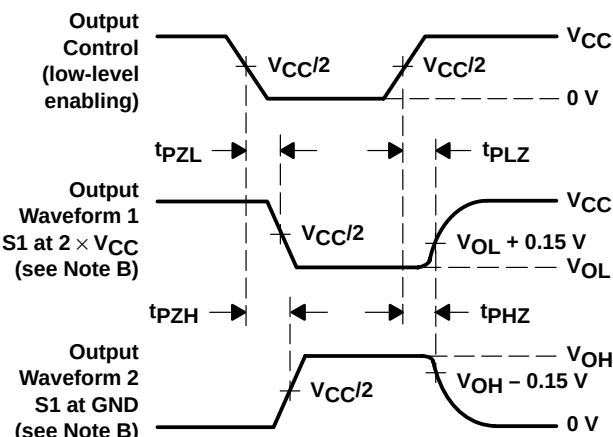
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



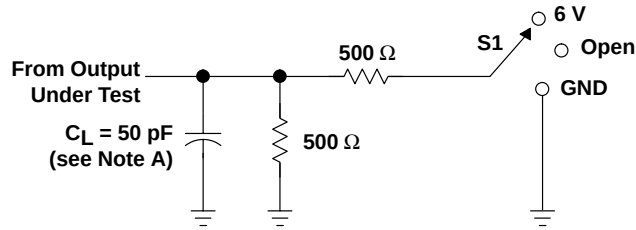
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

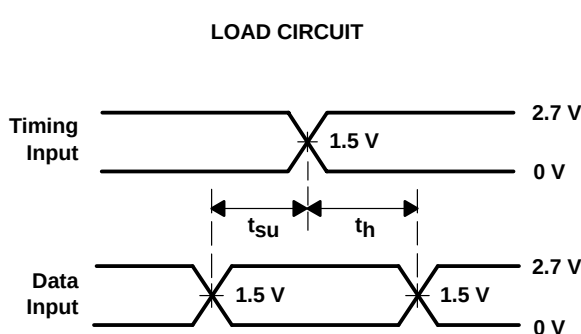
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

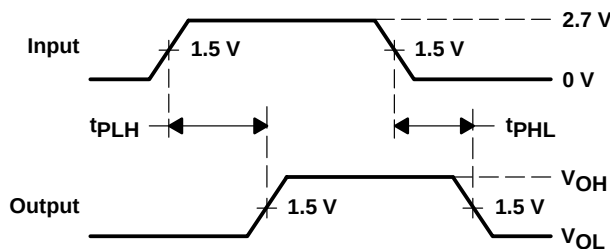


LOAD CIRCUIT

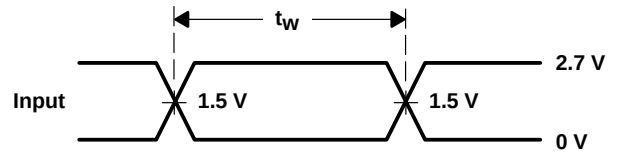
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



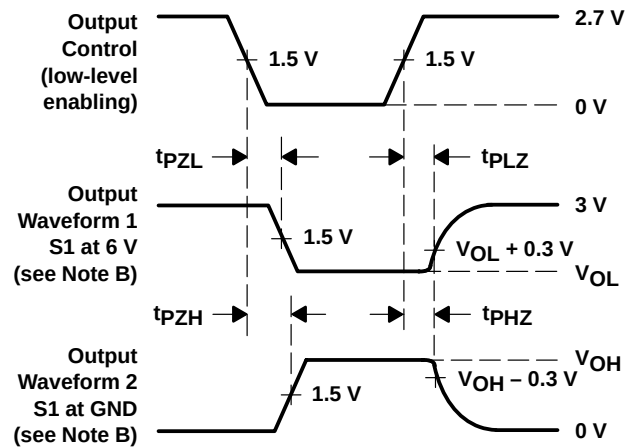
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

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16-BIT UNIVERSAL BUS DRIVER WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- Output Port Has Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- Designed to Comply With JEDEC 168-Pin and 200-Pin SDRAM Buffered DIMM Specification
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages

description

This 16-bit universal bus driver is designed for 1.65-V to 3.6-V V_{CC} operation.

Data flow from A to Y is controlled by the output-enable ($\overline{OE}$) input. The device operates in the transparent mode when the latch-enable ($\overline{LE}$) input is low. When $\overline{LE}$ is high, the A data is latched if the clock (CLK) input is held at a high or low logic level. If $\overline{LE}$ is high, the A data is stored in the latch/flip-flop on the low-to-high transition of CLK. When $\overline{OE}$ is high, the outputs are in the high-impedance state.

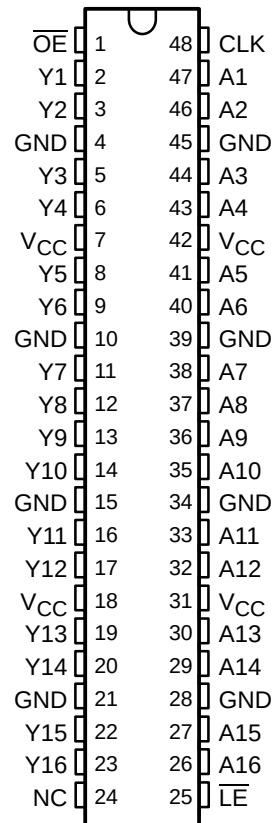
The output port includes equivalent 26-Ω series resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH162334 is characterized for operation from –40°C to 85°C.

DGG, DGV, OR DL PACKAGE (TOP VIEW)



NC – No internal connection

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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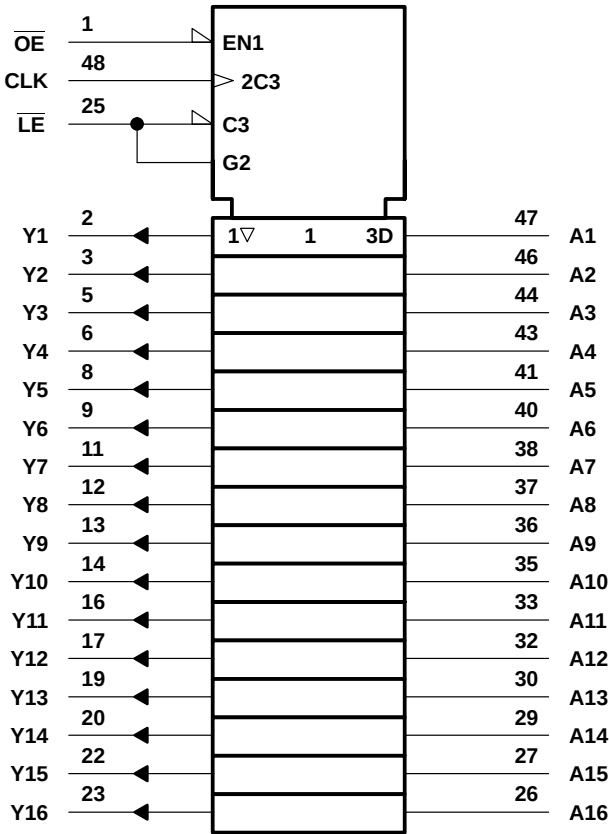
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FUNCTION TABLE

INPUTS				OUTPUT Y
OE	LE	CLK	A	
H	X	X	X	Z
L	L	X	L	L
L	L	X	H	H
L	H	↑	L	L
L	H	↑	H	H
L	H	L or H	X	Y ₀ [†]

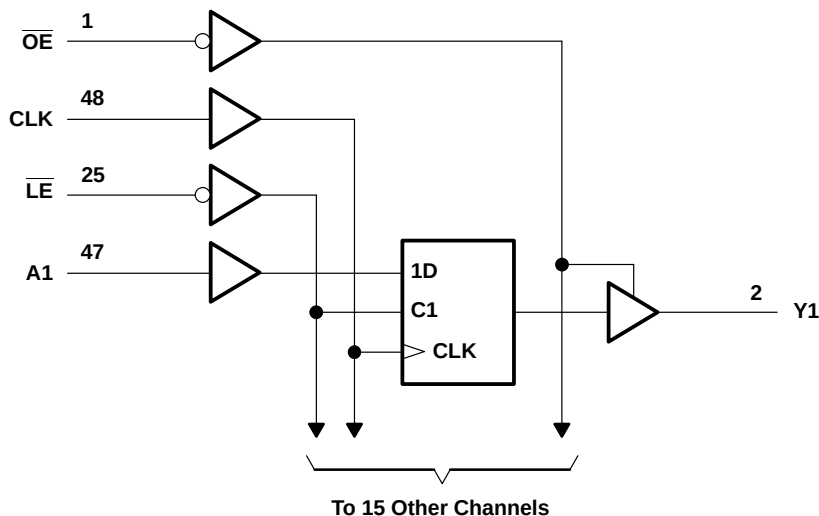
† Output level before the indicated steady-state input conditions were established

logic symbol[‡]



[‡] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3):	
DGG package	89°C/W
DGV package	93°C/W
DL package	94°C/W
Storage temperature range, T_{Stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–2	mA
		$V_{CC} = 2.3 \text{ V}$	–6	
		$V_{CC} = 2.7 \text{ V}$	–8	
		$V_{CC} = 3 \text{ V}$	–12	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	2	mA
		$V_{CC} = 2.3 \text{ V}$	6	
		$V_{CC} = 2.7 \text{ V}$	8	
		$V_{CC} = 3 \text{ V}$	12	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V			±5	µA
I _I (hold)		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V			±500	
I _{OZ}		V _O = V _{CC} or GND	3.6 V			±10	µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V			40	µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V			750	µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	5.5			pF
	Data inputs			6			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	8			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

				V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
				MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency			†		150		150		150		MHz
t _w	Pulse duration	LE low		†		3.3		3.3		3.3		ns
		CLK high or low		†		3.3		3.3		3.3		
t _{su}	Setup time	Data before CLK↑		†		1.4		1.7		1.5		ns
		Data before LE↑	CLK high	†		1.2		1.6		1.3		
			CLK low	†		1.4		1.5		1.2		
t _h	Hold time	Data after CLK↑		†		0.9		0.8		0.9		ns
		Data after LE↑	CLK high or low	†		1.2		1.1		1.1		

† This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	A	Y	†		1	3.9	4.5		1.1	3.9	ns
	$\overline{LE}$		†		1	5	6		1.3	5	
	CLK		†		1	4.9	5.4		1	4.9	
t _{en}	$\overline{OE}$	Y	†		1	5.4	6.4		1.1	5.4	ns
t _{dis}	$\overline{OE}$	Y	†		1	5	5.1		1.7	5	ns

† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

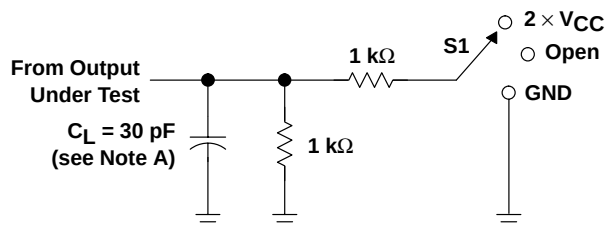
PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 0, f = 10 MHz	†	32	37	pF
		Outputs disabled		†	7	11.5	

† This information was not available at the time of publication.



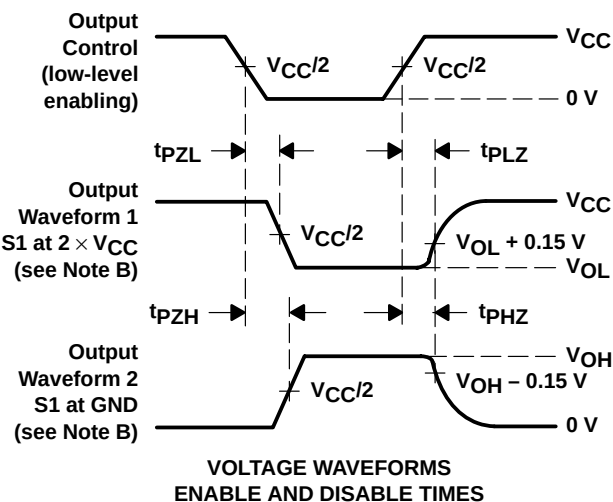
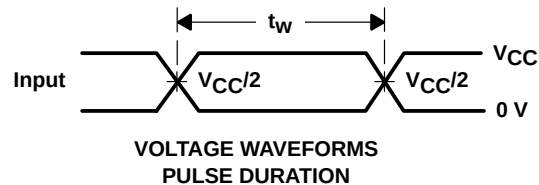
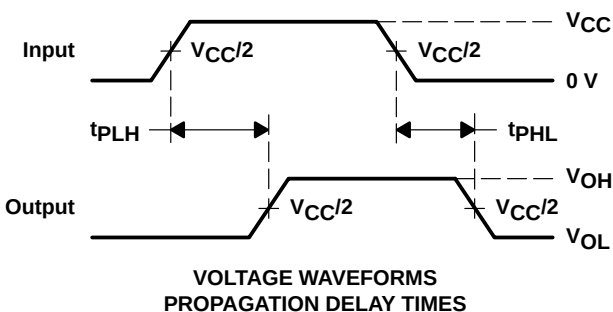
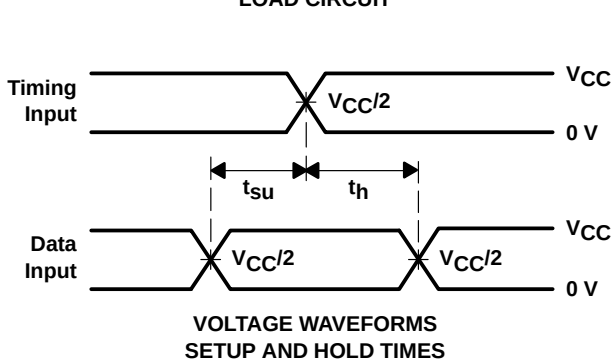
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	$2 \times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH162334

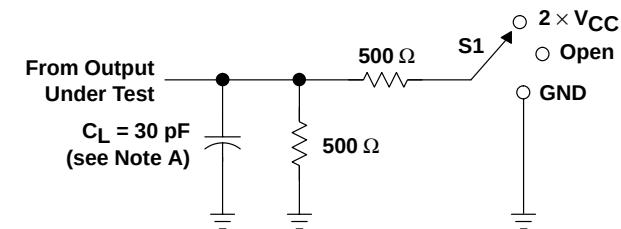
16-BIT UNIVERSAL BUS DRIVER

WITH 3-STATE OUTPUTS

SCES120E – JULY 1997 – REVISED FEBRUARY 1999

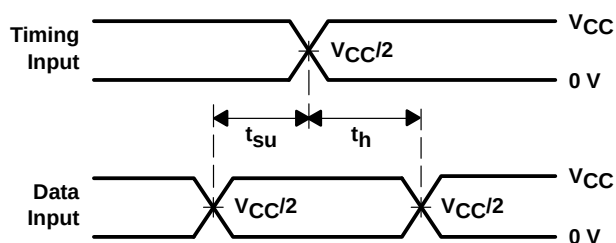
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

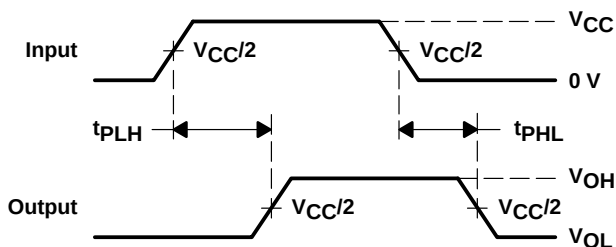


LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



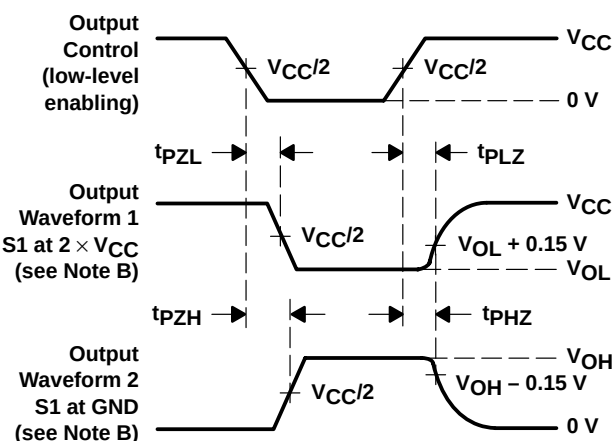
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



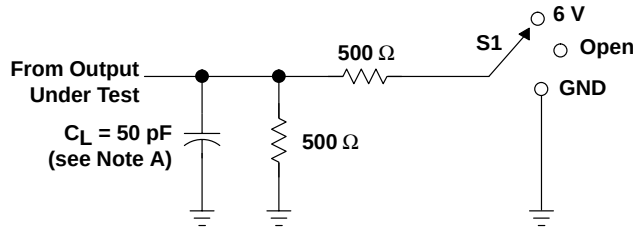
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

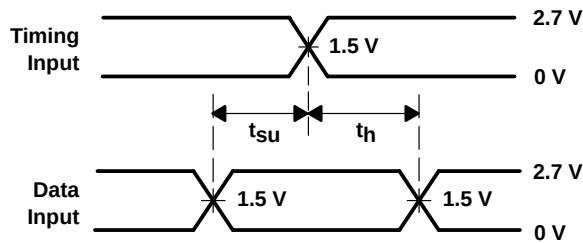
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V}$ AND $3.3\text{ V} \pm 0.3\text{ V}$

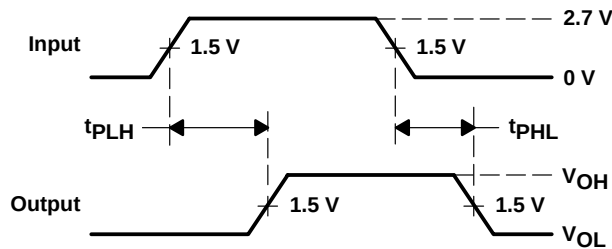


LOAD CIRCUIT

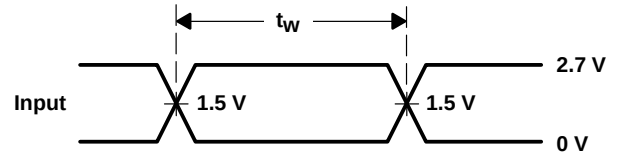
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



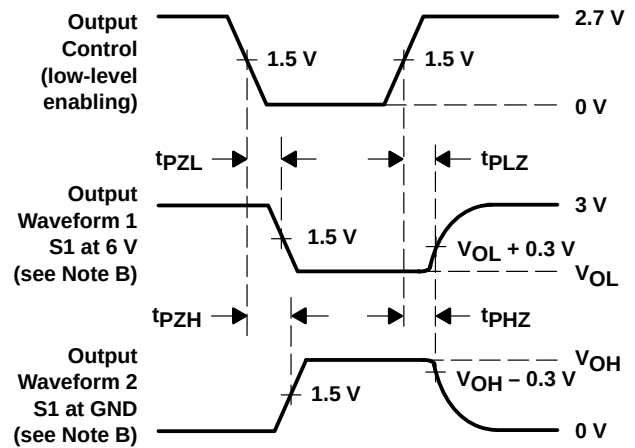
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES: A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
- D. The outputs are measured one at a time with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH162344

1-BIT TO 4-BIT ADDRESS DRIVER WITH 3-STATE OUTPUTS

SCES085E – AUGUST 1996 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- Output Ports Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DGG), Thin Shrink Small-Outline (DL), and Thin Very Small-Outline (DGV) Packages

description

This 1-bit to 4-bit address driver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH162344 is used in applications in which four separate memory locations must be addressed by a single address.

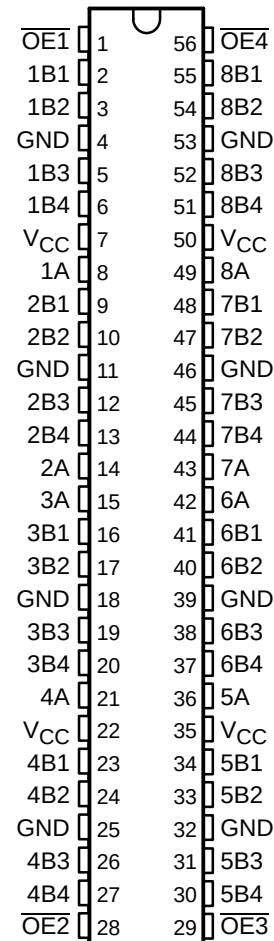
The outputs, which are designed to sink up to 12 mA, include equivalent 26-Ω resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH162344 is characterized for operation from -40°C to 85°C .

DGG, DGV, OR DL PACKAGE
(TOP VIEW)



A-TO-B FUNCTION TABLE

INPUTS		OUTPUT B _n
$\overline{OE}$	A	
L	H	H
L	L	L
H	X	Z

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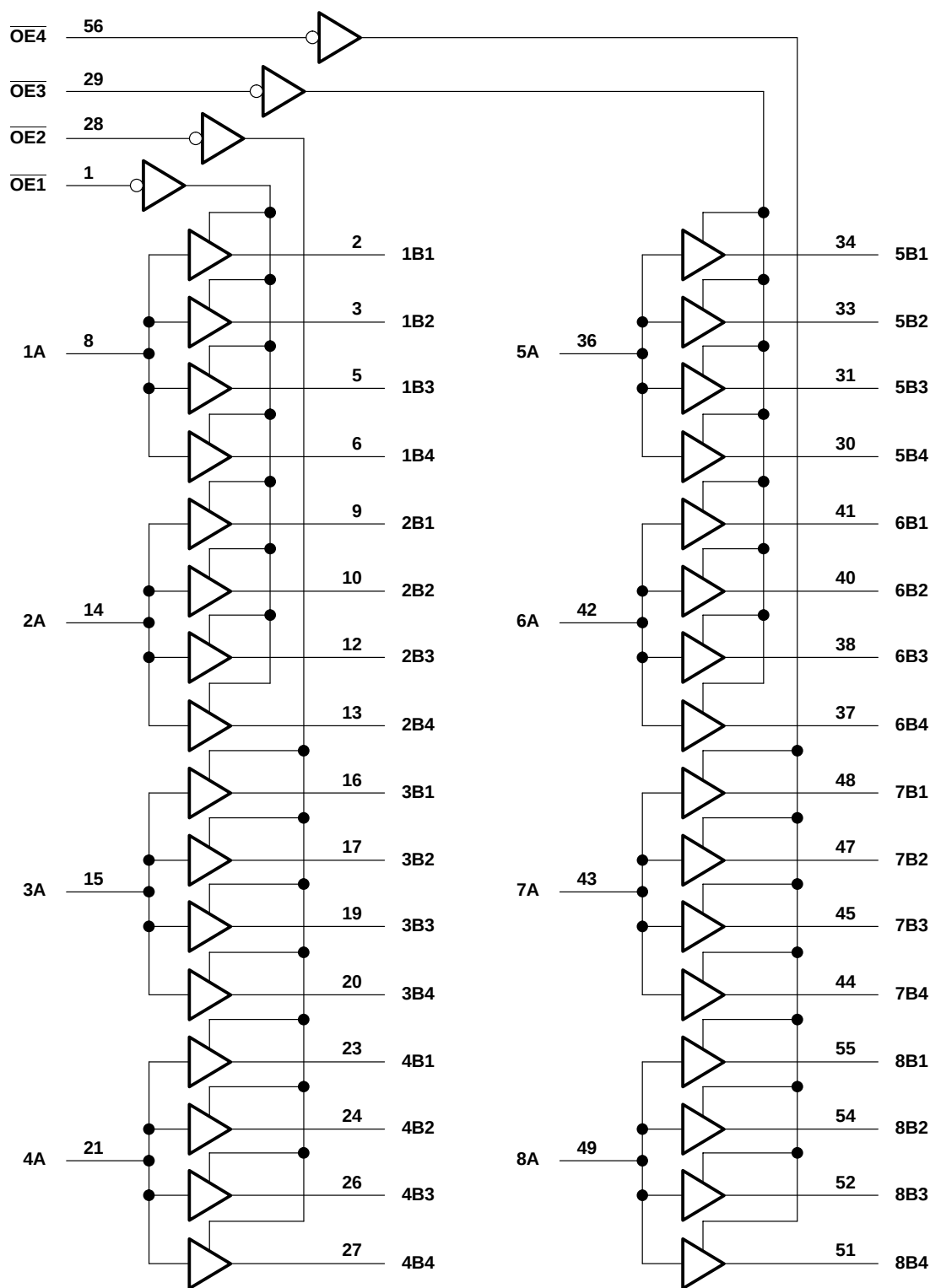
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SN74ALVCH162344

1-BIT TO 4-BIT ADDRESS DRIVER WITH 3-STATE OUTPUTS

SCES085E – AUGUST 1996 – REVISED FEBRUARY 1999

logic diagram (positive logic)



Supply voltage range, V_{CC}	−0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	−0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	−0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	−50 mA
Output clamp current, I_{OK} ($V_O < 0$)	−50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DGV package	86°C/W
DL package	74°C/W

NOTES:

1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−2		mA
		V _{CC} = 2.3 V	−6		
		V _{CC} = 2.7 V	−8		
		V _{CC} = 3 V	−12		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	2		mA
		V _{CC} = 2.3 V	6		
		V _{CC} = 2.7 V	8		
		V _{CC} = 3 V	12		
Δt/Δv	Input transition rise or fall rate		10		ns/V
T _A	Operating free-air temperature		−40	85	°C



**1-BIT TO 4-BIT ADDRESS DRIVER
WITH 3-STATE OUTPUTS**

SCES085E – AUGUST 1996 – REVISED FEBRUARY 1999

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	2.5			pF
	Data inputs			3.5			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	4			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	B	§	1	4.9	5.1		1.4	4.4	ns
t _{en}	OE	B	§	1	6.4	6.6		1.2	5.7	ns
t _{dis}	OE	B	§	1	5.4	4.7		1.2	4.5	ns
t _{sk(o)} [¶]								0.35		ns
t _{sk(o)} [#]								0.5		ns

[§] This information was not available at the time of publication.

[¶] Skew between outputs of the same bank and same package (same transition).

[#] Skew between outputs of all banks of same package (A1–A8 tied together).

SN74ALVCH162344

1-BIT TO 4-BIT ADDRESS DRIVER WITH 3-STATE OUTPUTS

SCES085E – AUGUST 1996 – REVISED FEBRUARY 1999

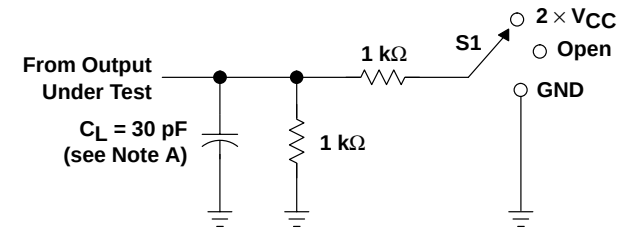
operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd} Power dissipation capacitance	Outputs enabled	$C_L = 0$, $f = 10\text{ MHz}$	†	68	82	pF
	Outputs disabled		†	12	14	

† This information was not available at the time of publication.

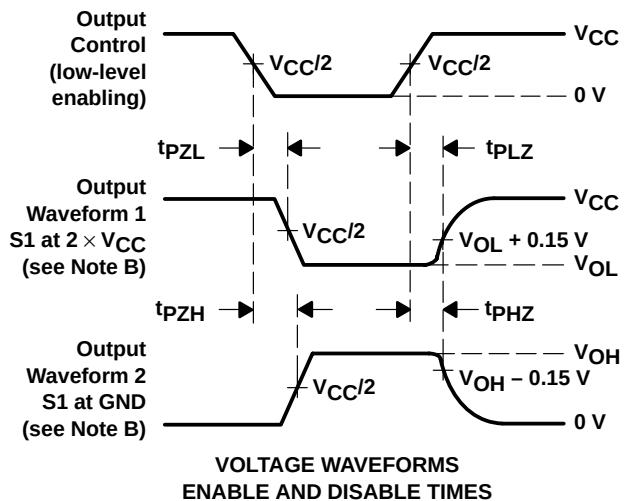
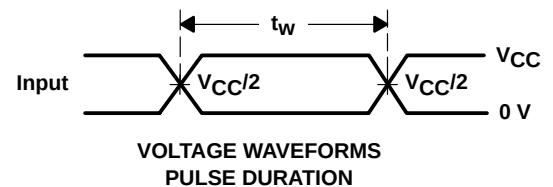
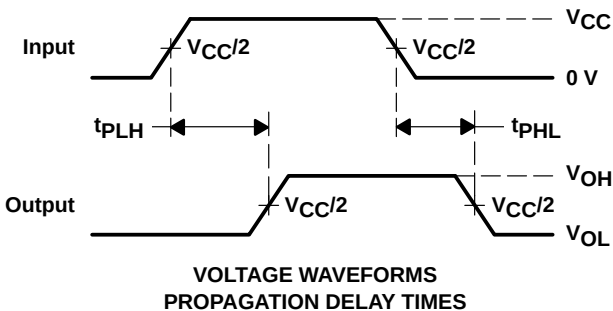
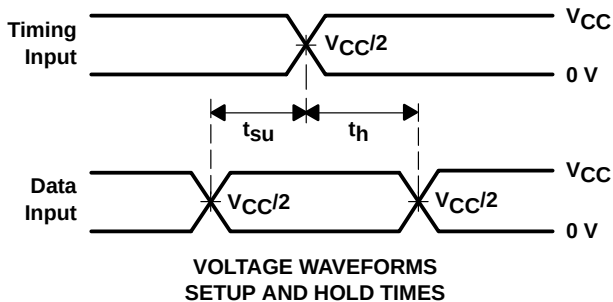
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms



SN74ALVCH162344

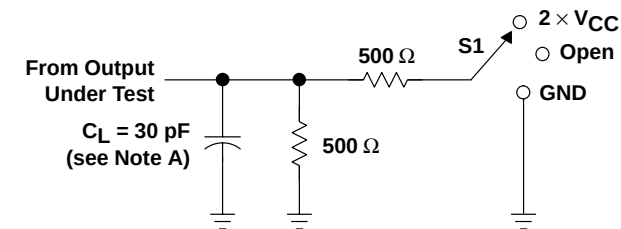
1-BIT TO 4-BIT ADDRESS DRIVER

WITH 3-STATE OUTPUTS

SCES085E – AUGUST 1996 – REVISED FEBRUARY 1999

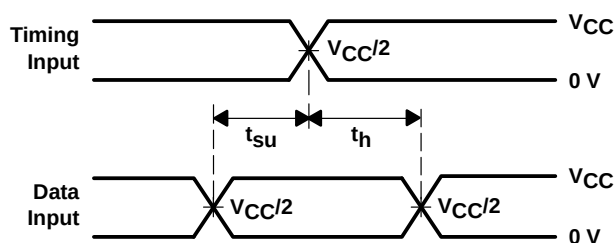
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

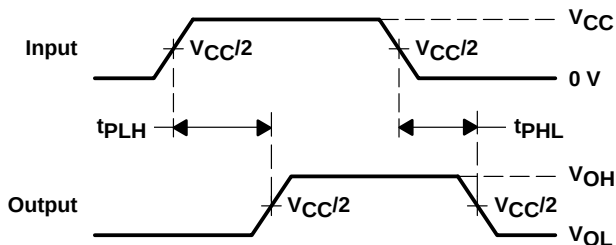


LOAD CIRCUIT

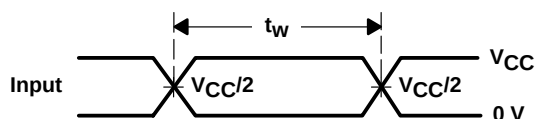
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



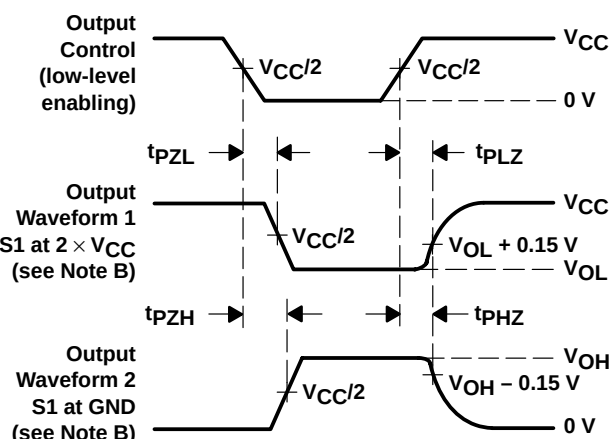
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



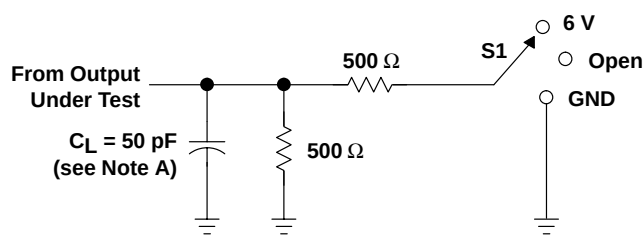
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

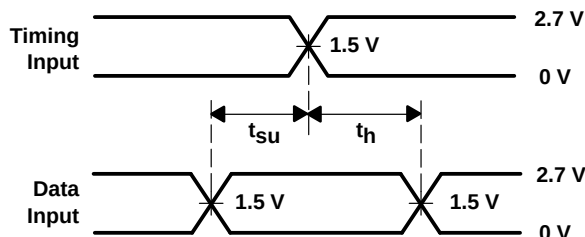
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

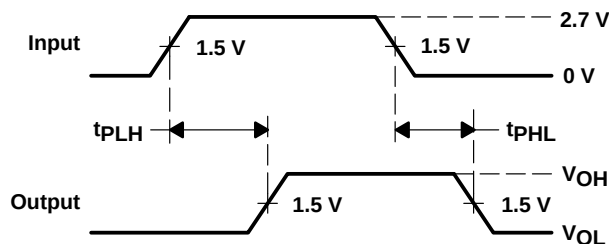


LOAD CIRCUIT

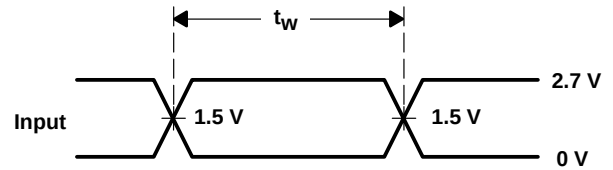
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



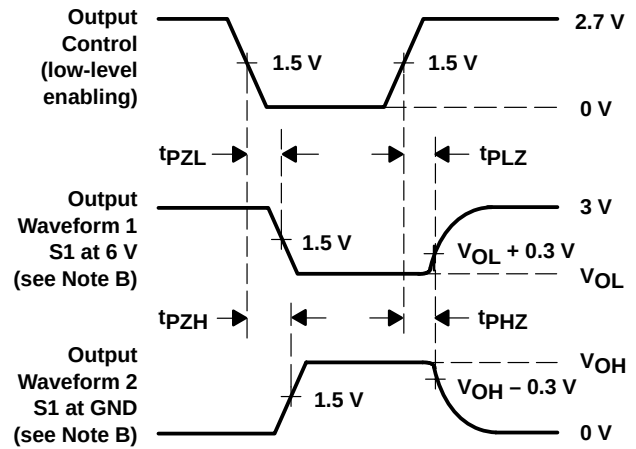
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
D. The outputs are measured one at a time with one transition per measurement.
E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
F. t_{PZL} and t_{PZH} are the same as t_{en} .
G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH162374

16-BIT EDGE-TRIGGERED D-TYPE FLIP-FLOP WITH 3-STATE OUTPUTS

SCES092B – JANUARY 1997 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Output Ports Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 16-bit edge-triggered D-type flip-flop is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH162374 is particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers. It can be used as two 8-bit flip-flops or one 16-bit flip-flop. On the positive transition of the clock (CLK) input, the Q outputs of the flip-flop take on the logic levels set up at the data (D) inputs.

The output-enable ($\overline{OE}$) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and the increased drive provide the capability to drive bus lines without need for interface or pullup components. $\overline{OE}$ does not affect internal operations of the flip-flop. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

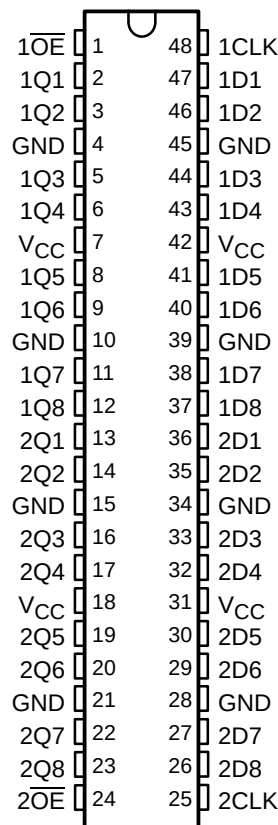
The outputs, which are designed to sink up to 12 mA, include equivalent 26-Ω resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH162374 is characterized for operation from –40°C to 85°C.

DGG OR DL PACKAGE
(TOP VIEW)



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SN74ALVCH162374
16-BIT EDGE-TRIGGERED D-TYPE FLIP-FLOP
WITH 3-STATE OUTPUTS

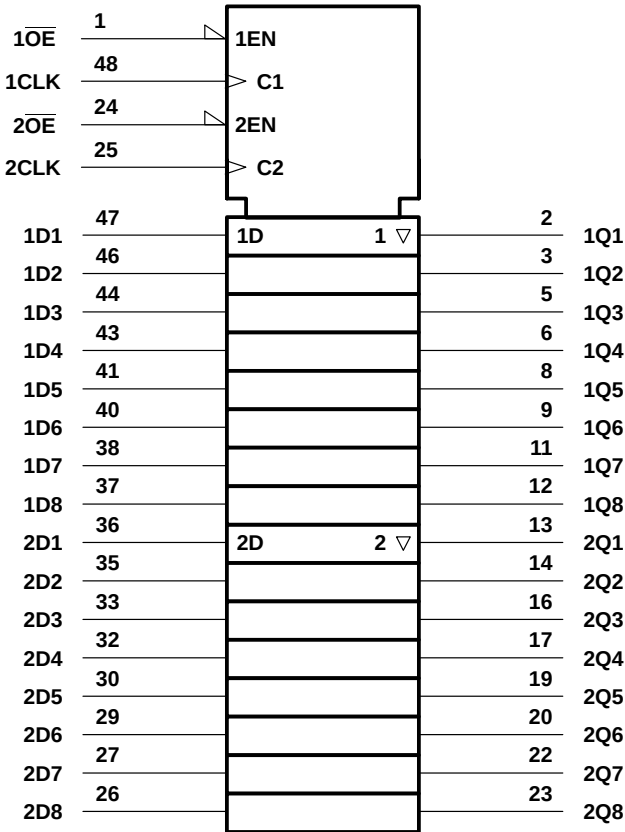
SCES092B – JANUARY 1997 – REVISED FEBRUARY 1999

FUNCTION TABLE

(each flip-flop)

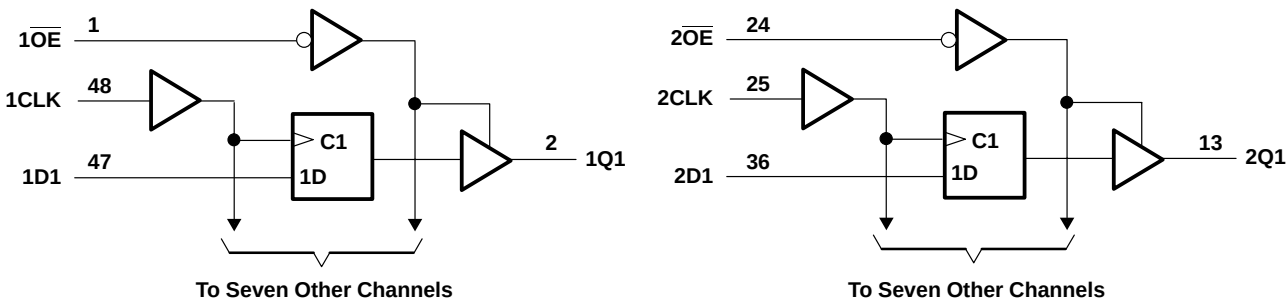
INPUTS			OUTPUT
$\overline{OE}$	CLK	D	Q
L	$\uparrow$	H	H
L	$\uparrow$	L	L
L	H or L	X	Q_0
H	X	X	Z

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



SN74ALVCH162374
16-BIT EDGE-TRIGGERED D-TYPE FLIP-FLOP
WITH 3-STATE OUTPUTS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	89°C/W
DL package	94°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−2		mA
		V _{CC} = 2.3 V	−6		
		V _{CC} = 2.7 V	−8		
		V _{CC} = 3 V	−12		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	2		mA
		V _{CC} = 2.3 V	6		
		V _{CC} = 2.7 V	8		
		V _{CC} = 3 V	12		
Δt/Δv	Input transition rise or fall rate			10	ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



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16-BIT EDGE-TRIGGERED D-TYPE FLIP-FLOP
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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3			pF
	Data inputs			6			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency	§		150		150		150		MHz
t _w	Pulse duration, CLK high or low	§		3.3		3.3		3.3		ns
t _{su}	Setup time, data before CLK↑	§		2.1		2.2		1.9		ns
t _h	Hold time, data after CLK↑	§		0.6		0.5		0.5		ns

§ This information was not available at the time of publication.



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16-BIT EDGE-TRIGGERED D-TYPE FLIP-FLOP
WITH 3-STATE OUTPUTS

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	CLK	Q	†		1	5.4	5.4		1	4.6	ns
t _{en}	$\overline{OE}$	Q	†		1	6.5	6.4		1	5.2	ns
t _{dis}	$\overline{OE}$	Q	†		1	5.6	5		1.2	4.5	ns

† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 0, f = 10 MHz	†	28	31	pF
		Outputs disabled		†	10	11	

† This information was not available at the time of publication.

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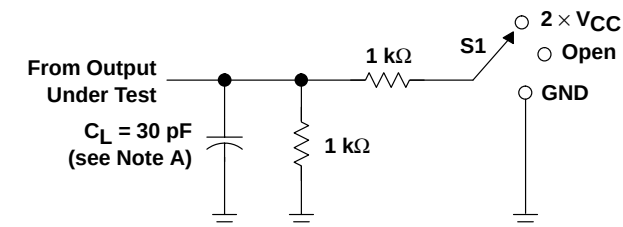
16-BIT EDGE-TRIGGERED D-TYPE FLIP-FLOP

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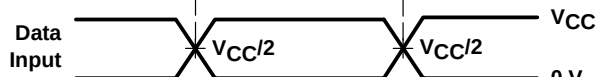
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$

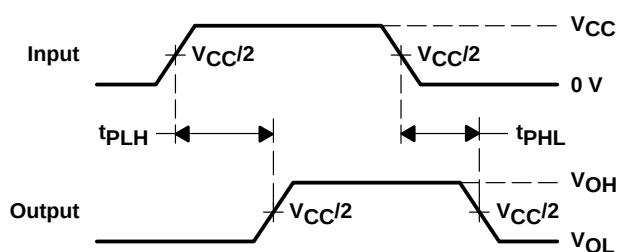


LOAD CIRCUIT

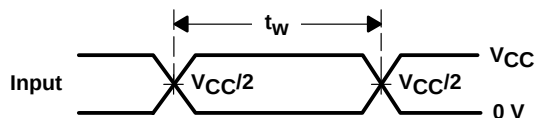
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times$ V_{CC}
t_{PHZ}/t_{PHZ}	GND



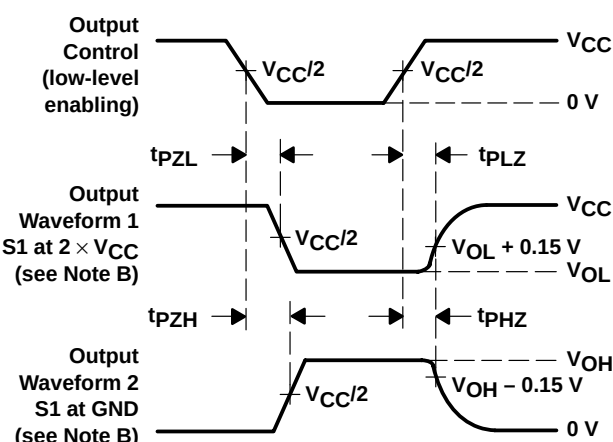
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



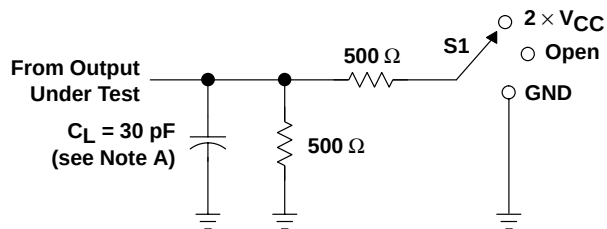
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

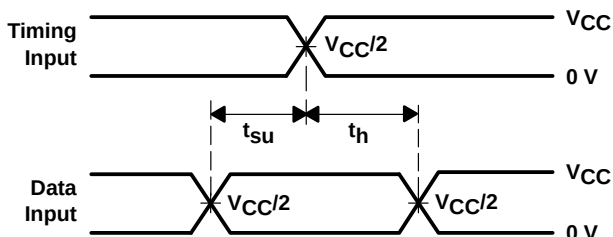
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

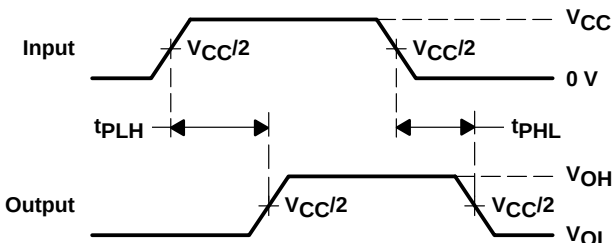


LOAD CIRCUIT

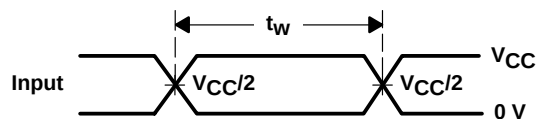
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



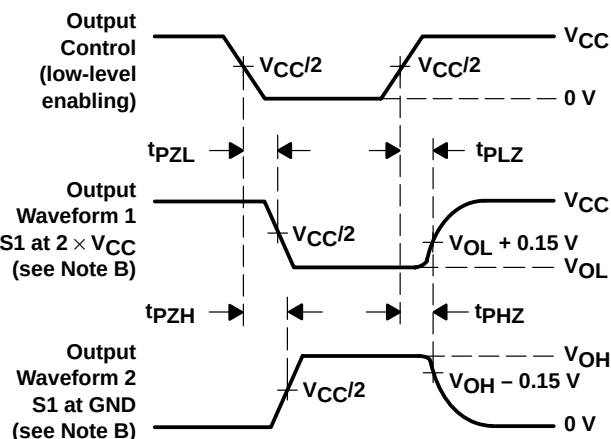
**VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES**



**VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES**



**VOLTAGE WAVEFORMS
PULSE DURATION**



**VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES**

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

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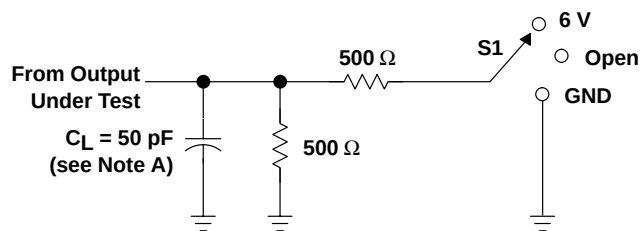
16-BIT EDGE-TRIGGERED D-TYPE FLIP-FLOP

WITH 3-STATE OUTPUTS

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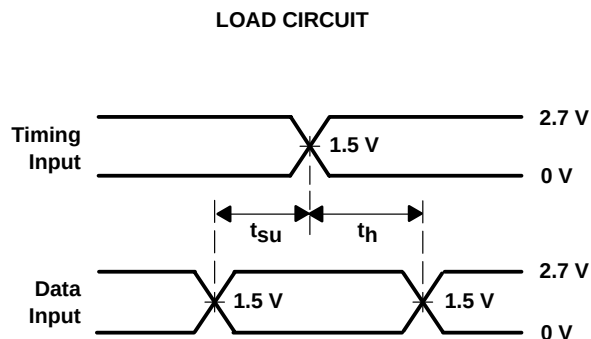
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$

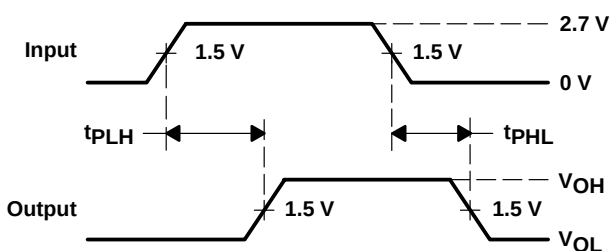


LOAD CIRCUIT

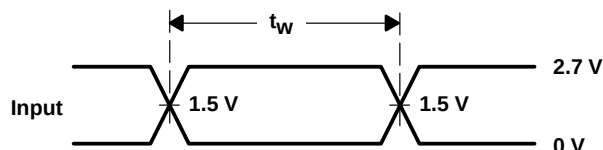
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



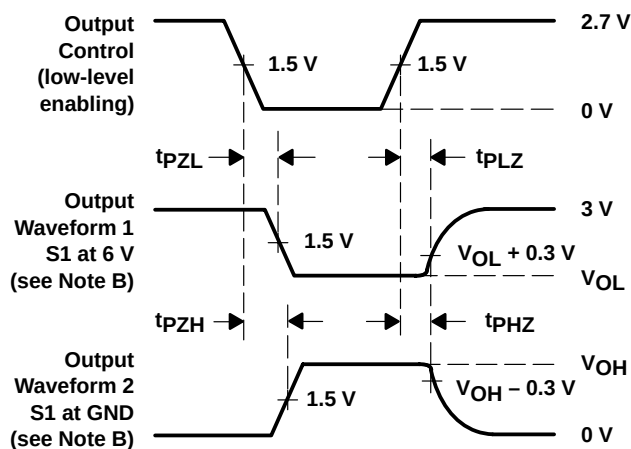
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH162409

9-BIT, 4-PORT UNIVERSAL BUS EXCHANGER

WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus+*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- B-Port Outputs Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- *UBE*™ (Universal Bus Exchanger) Allows Synchronous Data Exchange
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 9-bit, 4-port universal bus exchanger is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH162409 allows synchronous data exchange between four different buses. Data flow is controlled by the select (SEL0–SEL4) inputs. A data-flow state is stored on the rising edge of the clock (CLK) input if the select-enable ($\overline{SELEN}$) input is low. Once a data-flow state has been established, data is stored in the flip-flop on the rising edge of CLK if $\overline{SELEN}$ is high.

The data-flow control logic is designed to allow glitch-free data transmission.

The B outputs, which are designed to sink up to 12 mA, include equivalent 26-Ω series resistors to reduce overshoot and undershoot.

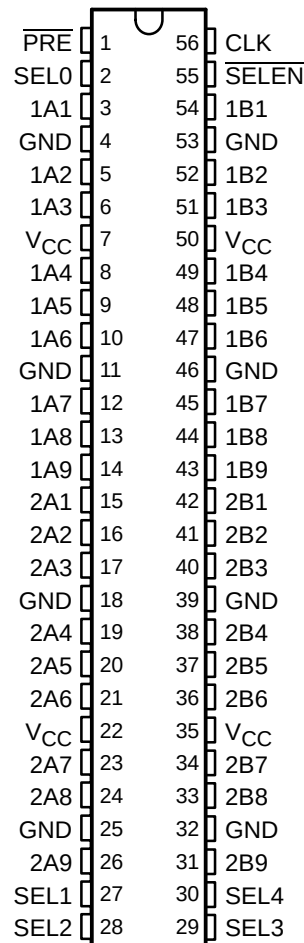
When preset ($\overline{PRE}$) transitions high, the outputs are disabled immediately, without waiting for a clock pulse. To leave the high-impedance state, both $\overline{PRE}$ and $\overline{SELEN}$ must be low and a clock pulse must be applied.

To ensure the high-impedance state during power up or power down, $\overline{PRE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH162409 is characterized for operation from –40°C to 85°C.

DGG OR DL PACKAGE
(TOP VIEW)



PRODUCT PREVIEW

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SN74ALVCH162409
 9-BIT, 4-PORT UNIVERSAL BUS EXCHANGER
 WITH 3-STATE OUTPUTS

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Function Tables

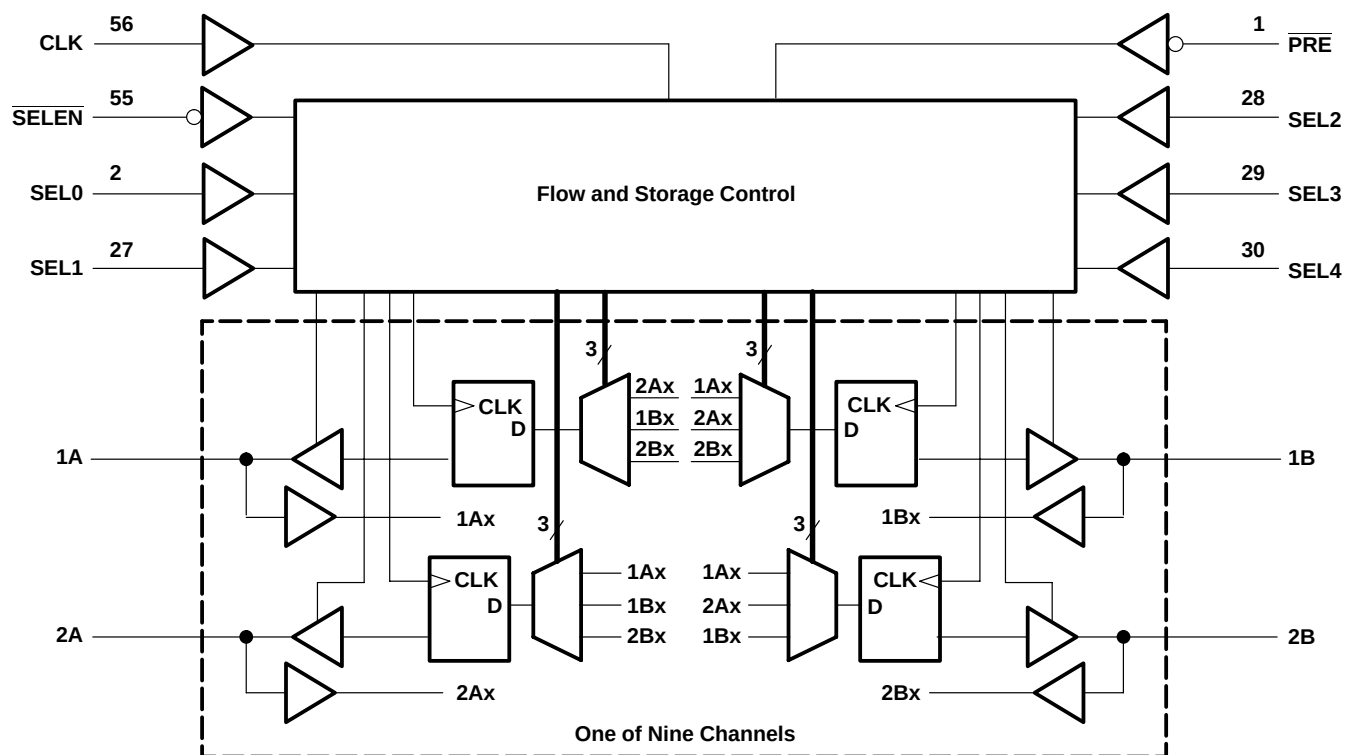
INPUTS		OUTPUT
CLK	SEND PORT	RECEIVE PORT
X	X	B ₀ [†]
X	L	L
X	H	H
↑	L	L
↑	H	H
H	X	B ₀ [†]
L	X	B ₀ [†]

[†] Output level before the indicated steady-state input conditions were established

DATA-FLOW CONTROL

INPUTS								DATA FLOW
PRE	SELEN	CLK	SEL0	SEL1	SEL2	SEL3	SEL4	
H	X	X	X	X	X	X	X	All outputs disabled
L	H	↑	X	X	X	X	X	No change
L	L	↑	0	0	0	0	0	None, all I/Os off
L	L	↑	0	0	0	0	1	Not used
L	L	↑	0	0	0	1	0	Not used
L	L	↑	0	0	0	1	1	Not used
L	L	↑	0	0	1	0	0	Not used
L	L	↑	0	0	1	0	1	Not used
L	L	↑	0	0	1	1	0	Not used
L	L	↑	0	0	1	1	1	Not used
L	L	↑	0	1	0	0	0	2A to 1A and 1B to 2B
L	L	↑	0	1	0	0	1	2A to 1A
L	L	↑	0	1	0	1	0	2B to 1B
L	L	↑	0	1	0	1	1	2A to 1A and 2B to 1B
L	L	↑	0	1	1	0	0	1A to 2A and 1B to 2B
L	L	↑	0	1	1	0	1	1A to 2A
L	L	↑	0	1	1	1	0	1B to 2B
L	L	↑	0	1	1	1	1	1A to 2A and 2B to 1B
L	L	↑	1	0	0	0	0	1A to 1B and 2B to 2A
L	L	↑	1	0	0	0	1	1A to 1B
L	L	↑	1	0	0	1	0	2A to 2B
L	L	↑	1	0	0	1	1	1A to 1B and 2A to 2B
L	L	↑	1	0	1	0	0	1B to 1A and 2A to 2B
L	L	↑	1	0	1	0	1	1B to 1A
L	L	↑	1	0	1	1	0	2B to 2A
L	L	↑	1	0	1	1	1	1B to 1A and 2B to 2A
L	L	↑	1	1	0	0	0	2B to 1A and 2A to 1B
L	L	↑	1	1	0	0	1	1B to 2A
L	L	↑	1	1	0	1	0	2B to 1A
L	L	↑	1	1	0	1	1	2B to 1A and 1B to 2A
L	L	↑	1	1	1	0	0	1A to 2B and 1B to 2A
L	L	↑	1	1	1	0	1	1A to 2B
L	L	↑	1	1	1	1	0	2A to 1B
L	L	↑	1	1	1	1	1	1A to 2B and 2A to 1B

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{Stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

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9-BIT, 4-PORT UNIVERSAL BUS EXCHANGER
WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current (A port)	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
	High-level output current (B port)	V _{CC} = 1.65 V	−2		
		V _{CC} = 2.3 V	−6		
		V _{CC} = 2.7 V	−8		
		V _{CC} = 3 V	−12		
I _{OL}	Low-level output current (A port)	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
	Low-level output current (B port)	V _{CC} = 1.65 V	2		
		V _{CC} = 2.3 V	6		
		V _{CC} = 2.7 V	8		
		V _{CC} = 3 V	12		
Δt/Δv	Input transition rise or fall rate		10		ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

PRODUCT PREVIEW



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9-BIT, 4-PORT UNIVERSAL BUS EXCHANGER
WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	A port	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
	B port	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}	A port	I _{OL} = 100 µA	1.65 V to 3.6 V			0.2	V
		I _{OL} = 4 mA	1.65 V			0.45	
		I _{OL} = 6 mA	2.3 V			0.4	
		I _{OL} = 12 mA	2.3 V			0.7	
			2.7 V			0.4	
		I _{OL} = 24 mA	3 V			0.55	
	B port	I _{OL} = 100 µA	1.65 V to 3.6 V			0.2	
		I _{OL} = 2 mA	1.65 V			0.45	
		I _{OL} = 4 mA	2.3 V			0.4	
		I _{OL} = 6 mA	2.3 V			0.55	
			3 V			0.55	
		I _{OL} = 8 mA	2.7 V			0.6	
		I _{OL} = 12 mA	3 V			0.8	
I _I		V _I = V _{CC} or GND	3.6 V			±5	µA
I _I (hold)		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V		–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V		–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V		–75			
		V _I = 0 to 3.6 V [‡]	3.6 V			±500	
I _{OZ} [§]		V _O = V _{CC} or GND	3.6 V			±10	µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V			40	µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V			750	µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V				pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V				pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.

PRODUCT PREVIEW



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9-BIT, 4-PORT UNIVERSAL BUS EXCHANGER
WITH 3-STATE OUTPUTS

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT	
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
f _{clock}	Clock frequency										MHz
t _w	Pulse duration, CLK high or low										ns
t _{su}	Setup time	A or B before CLK↑									ns
		SEL before CLK↑									
		SELEN before CLK↑									
		PRE before CLK↑									
t _h	Hold time	A or B after CLK↑									ns
		SEL after CLK↑									
		SELEN after CLK↑									

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 1.8\text{ V}$		$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f_{max}											MHz
t_{pd}	CLK	A or B									ns
t_{en}	CLK	A or B									ns
t_{dis}	CLK	A or B									ns
	PRE										

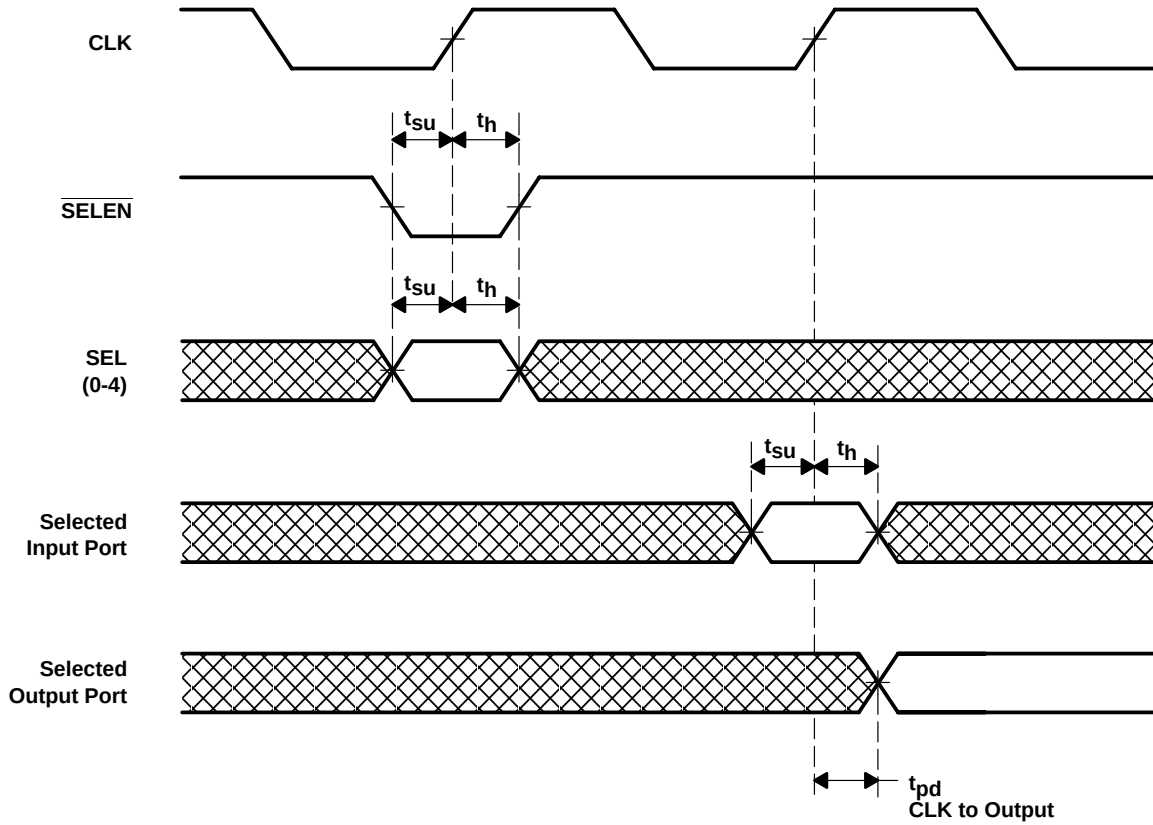
operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER			TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
				TYP	TYP	TYP	
C_{pd}	Power dissipation capacitance	All outputs enabled	$C_L = 50\text{ pF}, \quad f = 10\text{ MHz}$				pF
		All outputs disabled					

PRODUCT PREVIEW



timing diagram

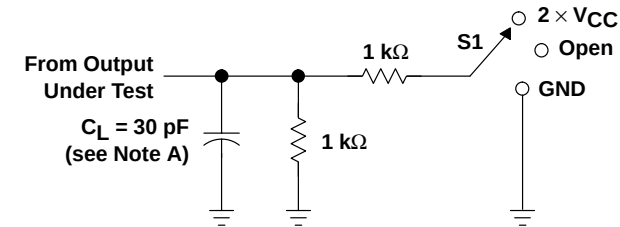


PRODUCT PREVIEW

SN74ALVCH162409
9-BIT, 4-PORT UNIVERSAL BUS EXCHANGER
WITH 3-STATE OUTPUTS

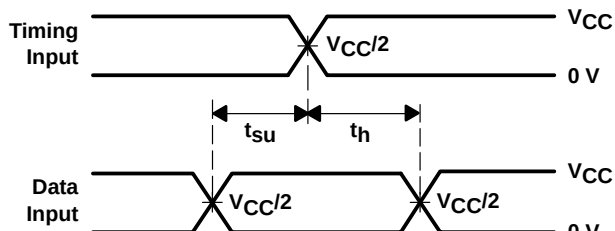
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PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8\text{ V}$

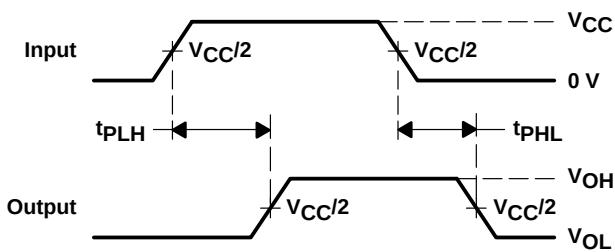


LOAD CIRCUIT

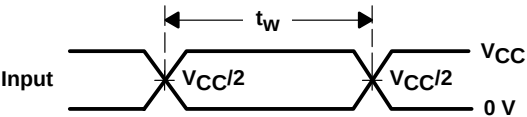
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PHL}	GND



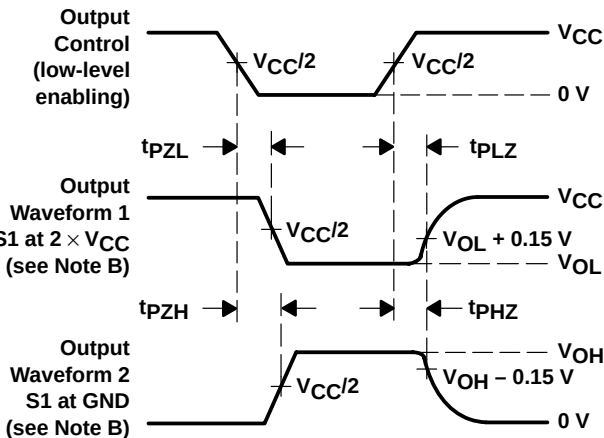
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



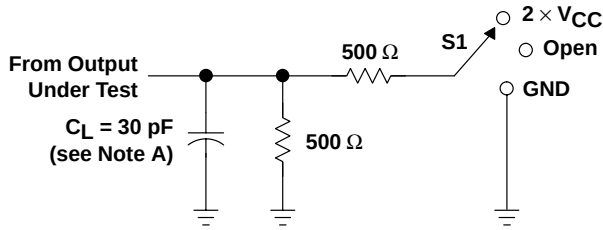
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

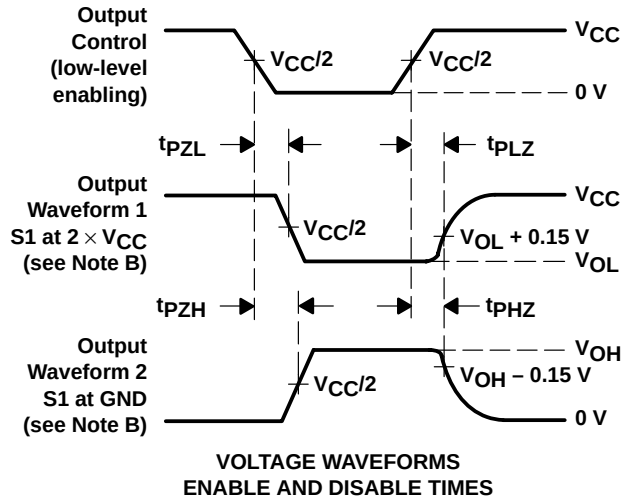
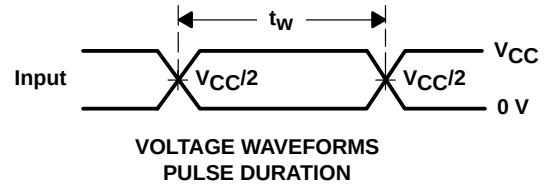
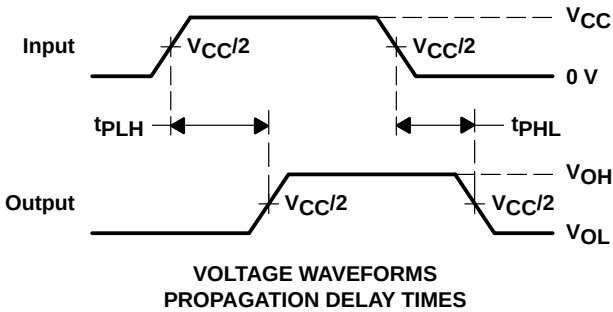
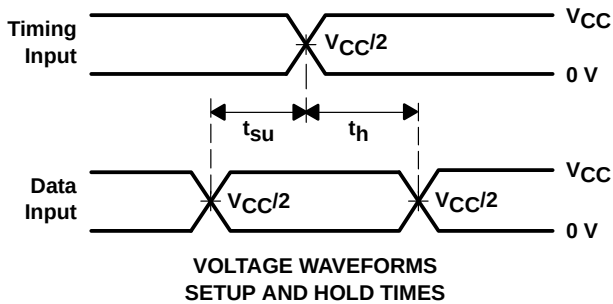
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



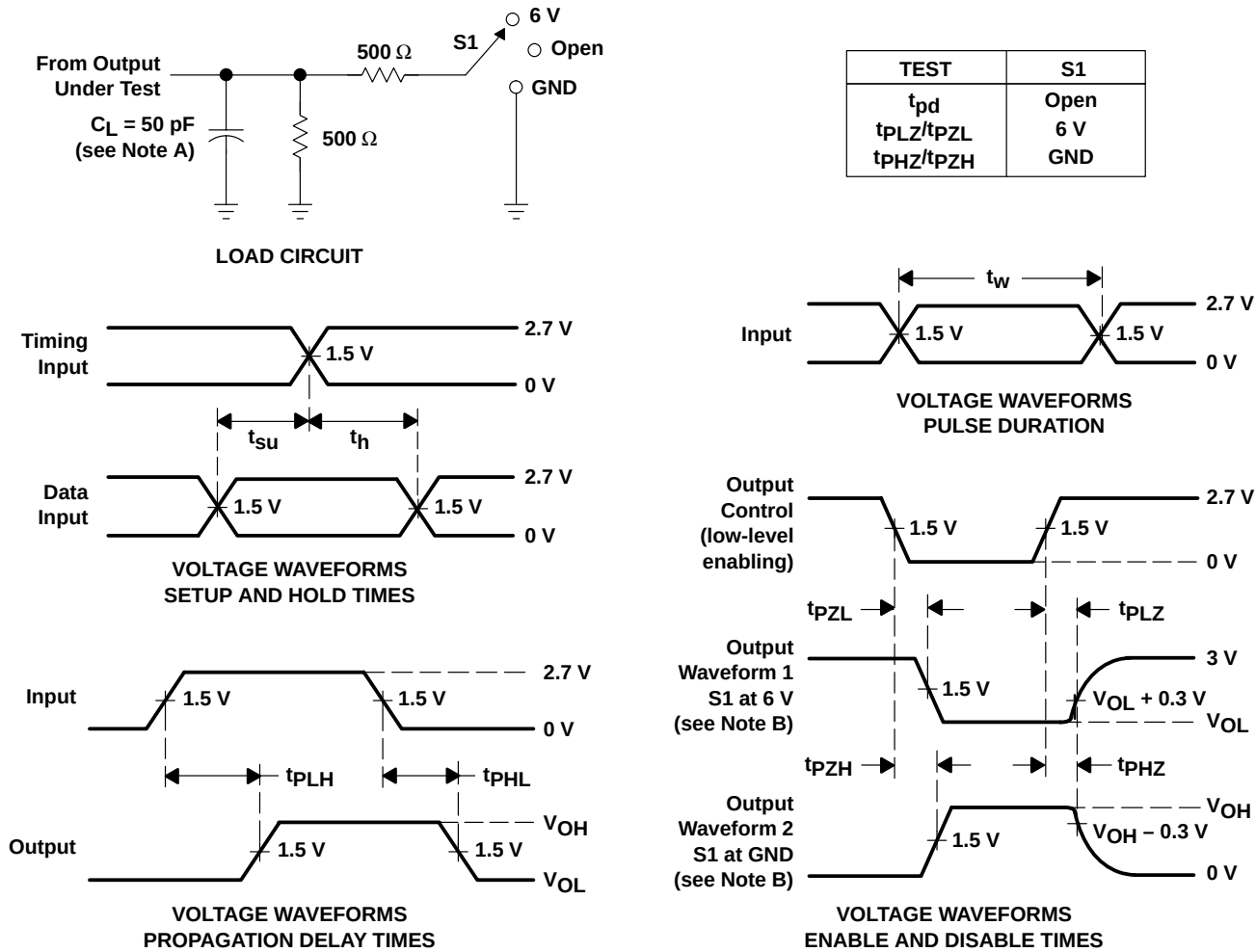
- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
D. The outputs are measured one at a time with one transition per measurement.
E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
F. t_{PZL} and t_{PZH} are the same as t_{en} .
G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

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WITH 3-STATE OUTPUTS

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PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCHR162409 9-BIT, 4-PORT UNIVERSAL BUS EXCHANGER WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus+™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- B-Port Outputs Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- *UBE™* (Universal Bus Exchanger) Allows Synchronous Data Exchange
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

NOTE: For order entry:
The DGG package is abbreviated to G.

description

This 9-bit, 4-port universal bus exchanger is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCHR162409 allows synchronous data exchange between four different buses. Data flow is controlled by the select (SEL0–SEL4) inputs. A data-flow state is stored on the rising edge of the clock (CLK) input if the select-enable ($\overline{SELEN}$) input is low. Once a data-flow state has been established, data is stored in the flip-flop on the rising edge of CLK if $\overline{SELEN}$ is high.

The data-flow control logic is designed to allow glitch-free data transmission.

The B outputs, which are designed to sink up to 12 mA, include equivalent 26-Ω series resistors to reduce overshoot and undershoot.

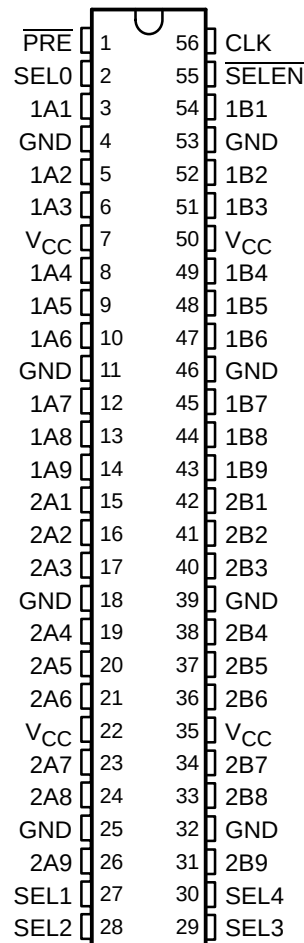
When preset ($\overline{PRE}$) transitions high, the outputs are disabled immediately, without waiting for a clock pulse. To leave the high-impedance state, both $\overline{PRE}$ and $\overline{SELEN}$ must be low and a clock pulse must be applied.

To ensure the high-impedance state during power up or power down, $\overline{PRE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCHR162409 is characterized for operation from –40°C to 85°C.

DGG OR DL PACKAGE
(TOP VIEW)



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SN74ALVCHR162409

9-BIT, 4-PORT UNIVERSAL BUS EXCHANGER

WITH 3-STATE OUTPUTS

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Function Tables

INPUTS		OUTPUT
CLK	SEND PORT	RECEIVE PORT
X	X	B ₀ [†]
X	L	L
X	H	H
↑	L	L
↑	H	H
H	X	B ₀ [†]
L	X	B ₀ [†]

[†] Output level before the indicated steady-state input conditions were established

DATA-FLOW CONTROL

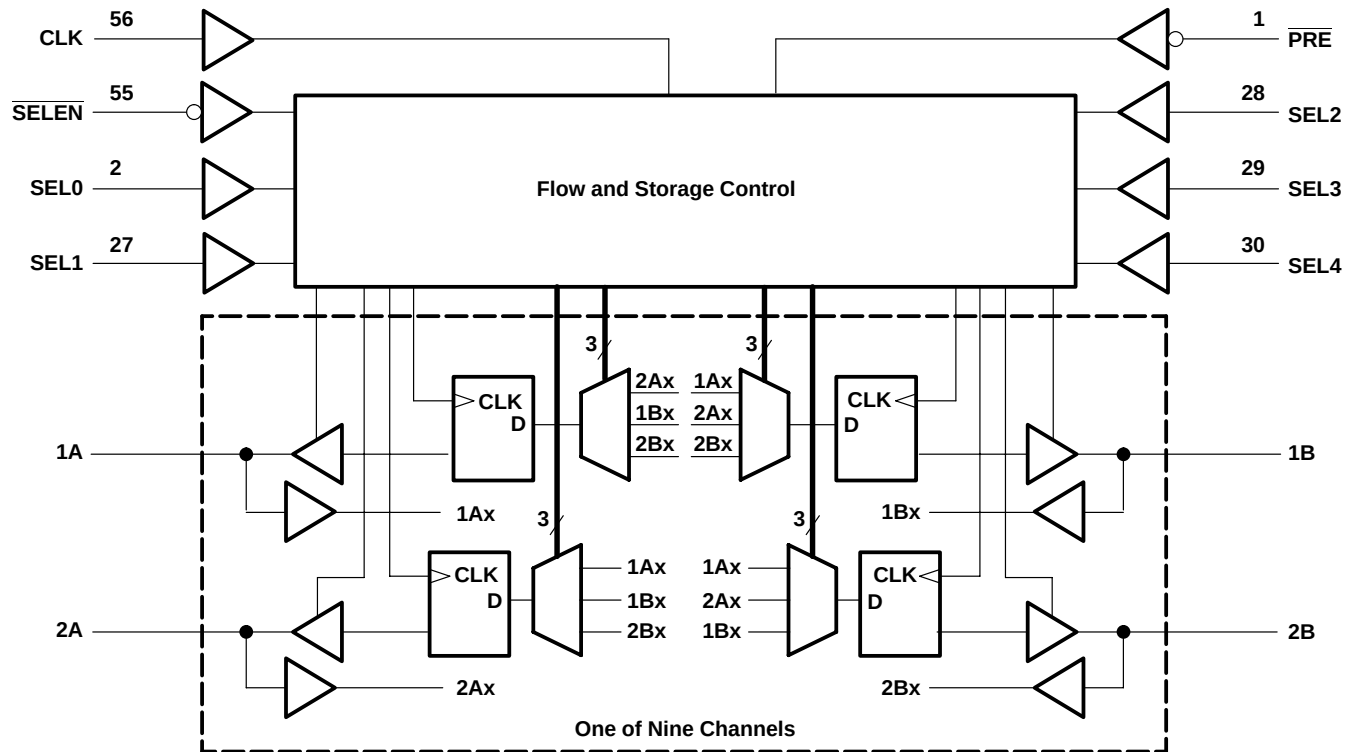
INPUTS								DATA FLOW
PRE	SELEN	CLK	SEL0	SEL1	SEL2	SEL3	SEL4	
H	X	X	X	X	X	X	X	All outputs disabled
L	H	↑	X	X	X	X	X	No change
L	L	↑	0	0	0	0	0	None, all I/Os off
L	L	↑	0	0	0	0	1	Not used
L	L	↑	0	0	0	1	0	Not used
L	L	↑	0	0	0	1	1	Not used
L	L	↑	0	0	1	0	0	Not used
L	L	↑	0	0	1	0	1	Not used
L	L	↑	0	0	1	1	0	Not used
L	L	↑	0	0	1	1	1	Not used
L	L	↑	0	1	0	0	0	2A to 1A and 1B to 2B
L	L	↑	0	1	0	0	1	2A to 1A
L	L	↑	0	1	0	1	0	2B to 1B
L	L	↑	0	1	0	1	1	2A to 1A and 2B to 1B
L	L	↑	0	1	1	0	0	1A to 2A and 1B to 2B
L	L	↑	0	1	1	0	1	1A to 2A
L	L	↑	0	1	1	1	0	1B to 2B
L	L	↑	0	1	1	1	1	1A to 2A and 2B to 1B
L	L	↑	1	0	0	0	0	1A to 1B and 2B to 2A
L	L	↑	1	0	0	0	1	1A to 1B
L	L	↑	1	0	0	1	0	2A to 2B
L	L	↑	1	0	0	1	1	1A to 1B and 2A to 2B
L	L	↑	1	0	1	0	0	1B to 1A and 2A to 2B
L	L	↑	1	0	1	0	1	1B to 1A
L	L	↑	1	0	1	1	0	2B to 2A
L	L	↑	1	0	1	1	1	1B to 1A and 2B to 2A
L	L	↑	1	1	0	0	0	2B to 1A and 2A to 1B
L	L	↑	1	1	0	0	1	1B to 2A
L	L	↑	1	1	0	1	0	2B to 1A
L	L	↑	1	1	0	1	1	2B to 1A and 1B to 2A
L	L	↑	1	1	1	0	0	1A to 2B and 1B to 2A
L	L	↑	1	1	1	0	1	1A to 2B
L	L	↑	1	1	1	1	0	2A to 1B
L	L	↑	1	1	1	1	1	1A to 2B and 2A to 1B



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WITH 3-STATE OUTPUTS

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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

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9-BIT, 4-PORT UNIVERSAL BUS EXCHANGER
WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–2	mA
		$V_{CC} = 2.3 \text{ V}$	–6	
		$V_{CC} = 2.7 \text{ V}$	–8	
		$V_{CC} = 3 \text{ V}$	–12	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	2	mA
		$V_{CC} = 2.3 \text{ V}$	6	
		$V_{CC} = 2.7 \text{ V}$	8	
		$V_{CC} = 3 \text{ V}$	12	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V			±5	µA
I _I (hold)		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V		–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V		–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V		–75			
		V _I = 0 to 3.6 V [‡]	3.6 V			±500	
I _{OZ} [§]		V _O = V _{CC} or GND	3.6 V			±10	µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V			40	µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V			750	µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V			4	pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V			8	pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.



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9-BIT, 4-PORT UNIVERSAL BUS EXCHANGER WITH 3-STATE OUTPUTS

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency		†		120		120		120		MHz
t _w	Pulse duration, CLK high or low		†		4.2		4.2		3		ns
t _{su}	Setup time	A or B before CLK↑	†		1.9		1.9		1.4		ns
		SEL before CLK↑	†		5.1		4.2		3.5		
		$\overline{\text{SELEN}}$ before CLK↑	†		2.5		2.5		1.8		
		$\overline{\text{PRE}}$ before CLK↑	†		1		1		0.7		
t _h	Hold time	A or B after CLK↑	†		0.8		0.8		1		ns
		SEL after CLK↑	†		0		0		0		
		$\overline{\text{SELEN}}$ after CLK↑	†		0.5		0.5		0.8		

† This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 1.8\text{ V}$		$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f_{max}			†		120		120		120		MHz
t_{pd}	CLK	A or B	†		1.5	6.9	7		1.5	6.2	ns
t_{en}	CLK	A or B	†		2.4	7.8	7.6		2	6.8	ns
t_{dis}	CLK	A or B	†		2.3	7.1	6.4		2	6.1	ns
	PRE		†		2.8	7.7	7		2.5	6.4	

† This information was not available at the time of publication.

operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd}	Power dissipation capacitance	All outputs enabled	†	60	60	pF
		All outputs disabled	†	60	60	

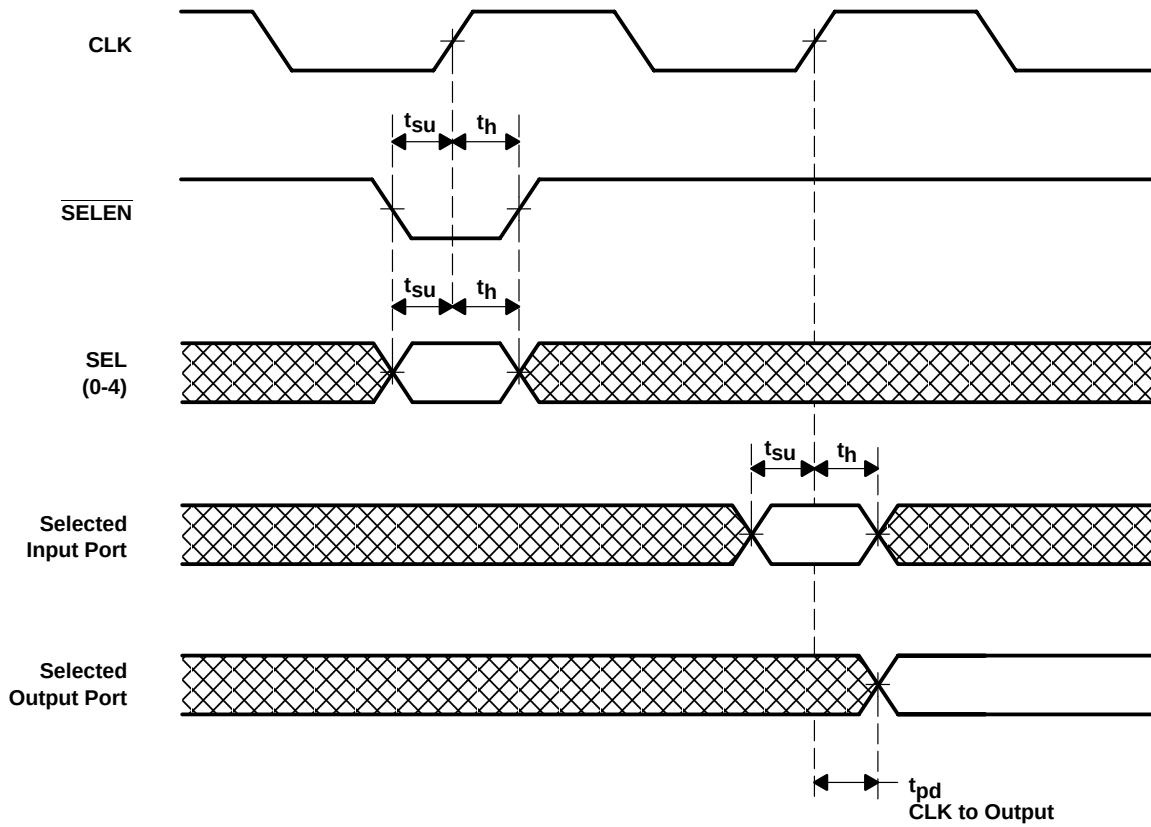
† This information was not available at the time of publication.



SN74ALVCHR162409
9-BIT, 4-PORT UNIVERSAL BUS EXCHANGER
WITH 3-STATE OUTPUTS

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timing diagram



SN74ALVCHR162409

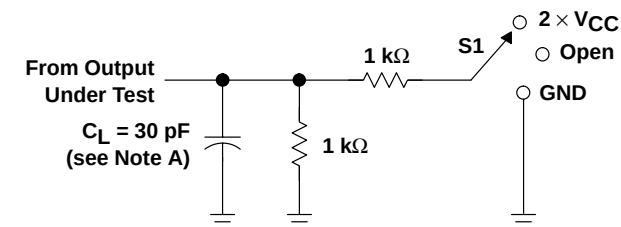
9-BIT, 4-PORT UNIVERSAL BUS EXCHANGER

WITH 3-STATE OUTPUTS

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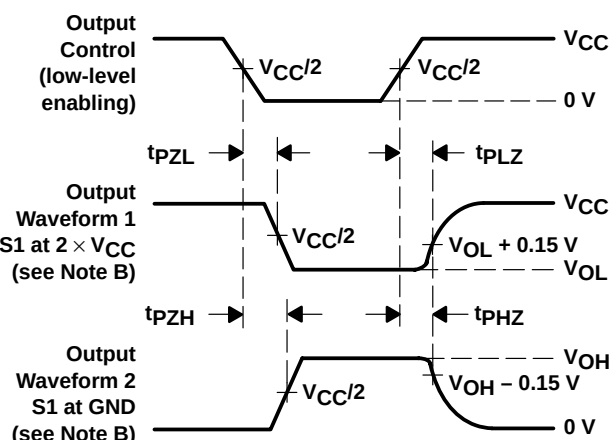
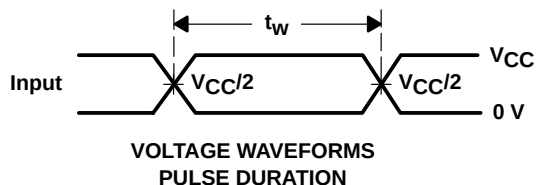
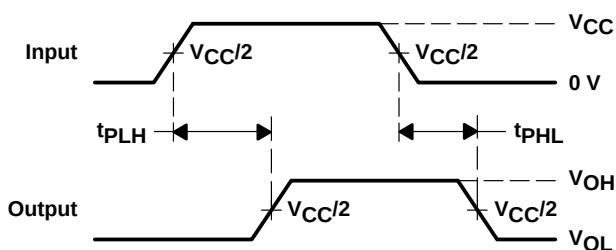
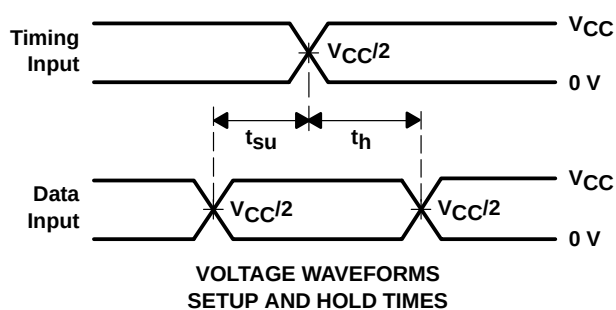
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PHL}	GND

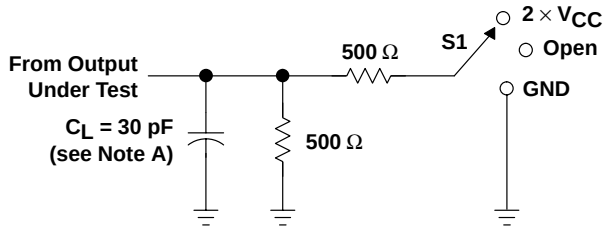


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

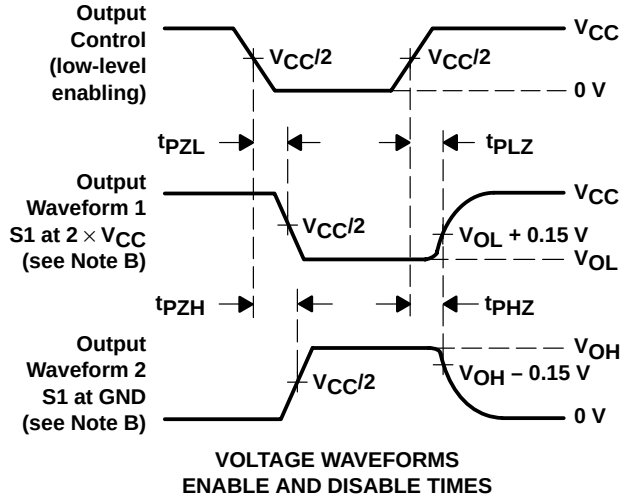
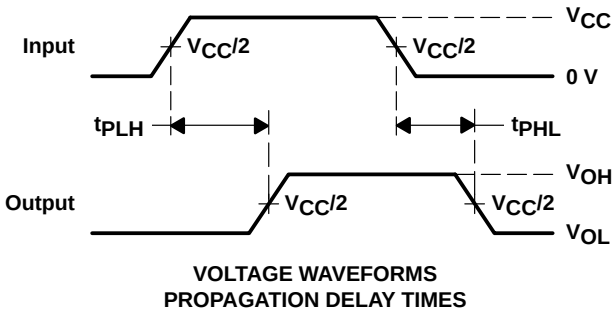
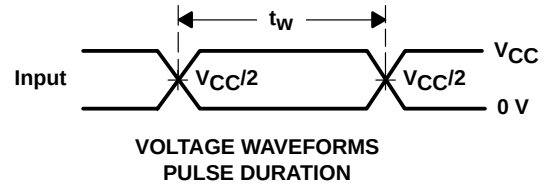
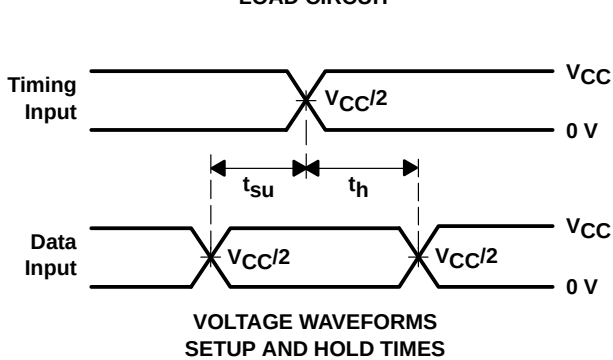
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	$2 \times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
D. The outputs are measured one at a time with one transition per measurement.
E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
F. t_{PZL} and t_{PZH} are the same as t_{en} .
G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCHR162409

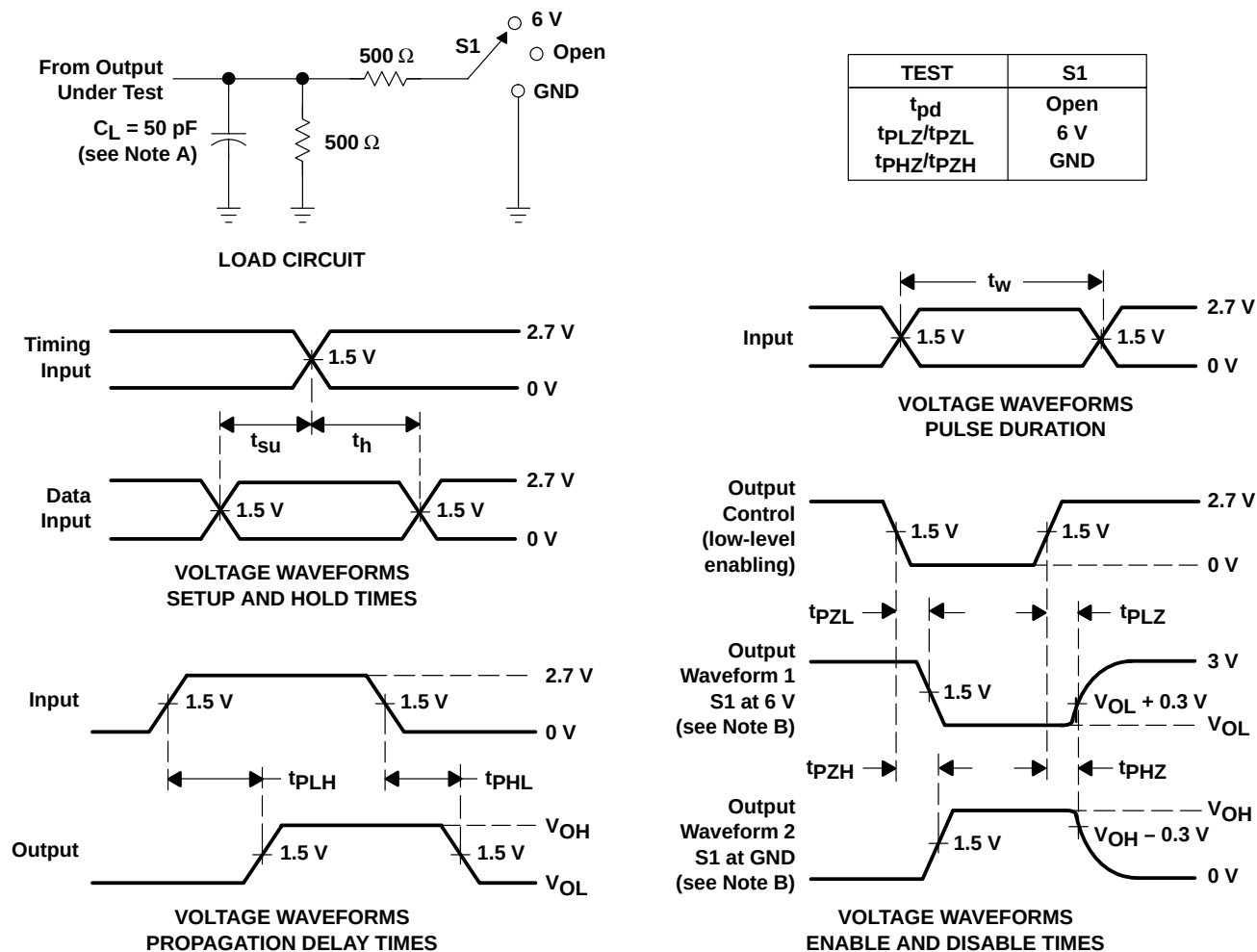
9-BIT, 4-PORT UNIVERSAL BUS EXCHANGER

WITH 3-STATE OUTPUTS

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PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH162525

18-BIT REGISTERED BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- B-Port Outputs Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Option Includes Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 18-bit universal bus transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

Data flow in each direction is controlled by output-enable ($\overline{OEAB}$ and $\overline{OEBA}$) and clock-enable ($\overline{CLKENAB}$ and $\overline{CLKENBA}$) inputs. For the A-to-B data flow, the data flows through a single register. The B-to-A data can flow through a four-stage pipeline register path, or through a single register path, depending on the state of the select ($\overline{SEL}$) input.

Data is stored in the internal registers on the low-to-high transition of the clock (CLK) input, provided that the appropriate $\overline{CLKEN}$ inputs are low. The A-to-B data transfer is synchronized to the CLKAB input, and B-to-A data transfer is synchronized with the CLK1BA and CLK2BA inputs.

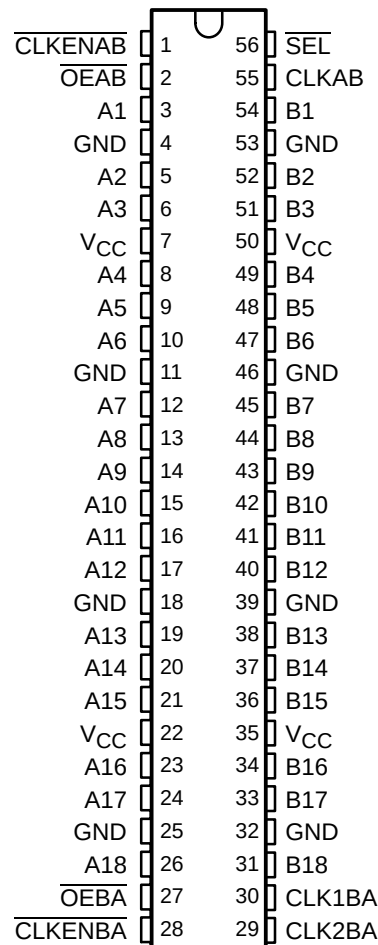
The B outputs, which are designed to sink up to 12 mA, include equivalent 26-Ω resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH162525 is characterized for operation from –40°C to 85°C.

DGG OR DL PACKAGE
(TOP VIEW)



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18-BIT REGISTERED BUS TRANSCEIVER

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Function Tables

A-TO-B STORAGE
($\overline{\text{OEAB}} = \text{L}$)

INPUTS			OUTPUT B
$\overline{\text{CLKENAB}}$	CLKAB	A	
H	X	X	$\text{B}_0^\dagger$
L	$\uparrow$	L	L
L	$\uparrow$	H	H

$\dagger$ Output level before the indicated steady-state input conditions were established

B-TO-A STORAGE
($\overline{\text{OEBA}} = \text{L}$)

INPUTS					OUTPUT A
$\overline{\text{CLKENBA}}$	CLK2BA	CLK1BA	$\overline{\text{SEL}}$	B	
H	X	X	X	X	$\text{A}_0^\dagger$
L	$\uparrow$	X	H	L	L
L	$\uparrow$	X	H	H	H
L	$\uparrow$	$\uparrow$	L	L	$\text{L}^\ddagger$
L	$\uparrow$	$\uparrow$	L	H	$\text{H}^\ddagger$

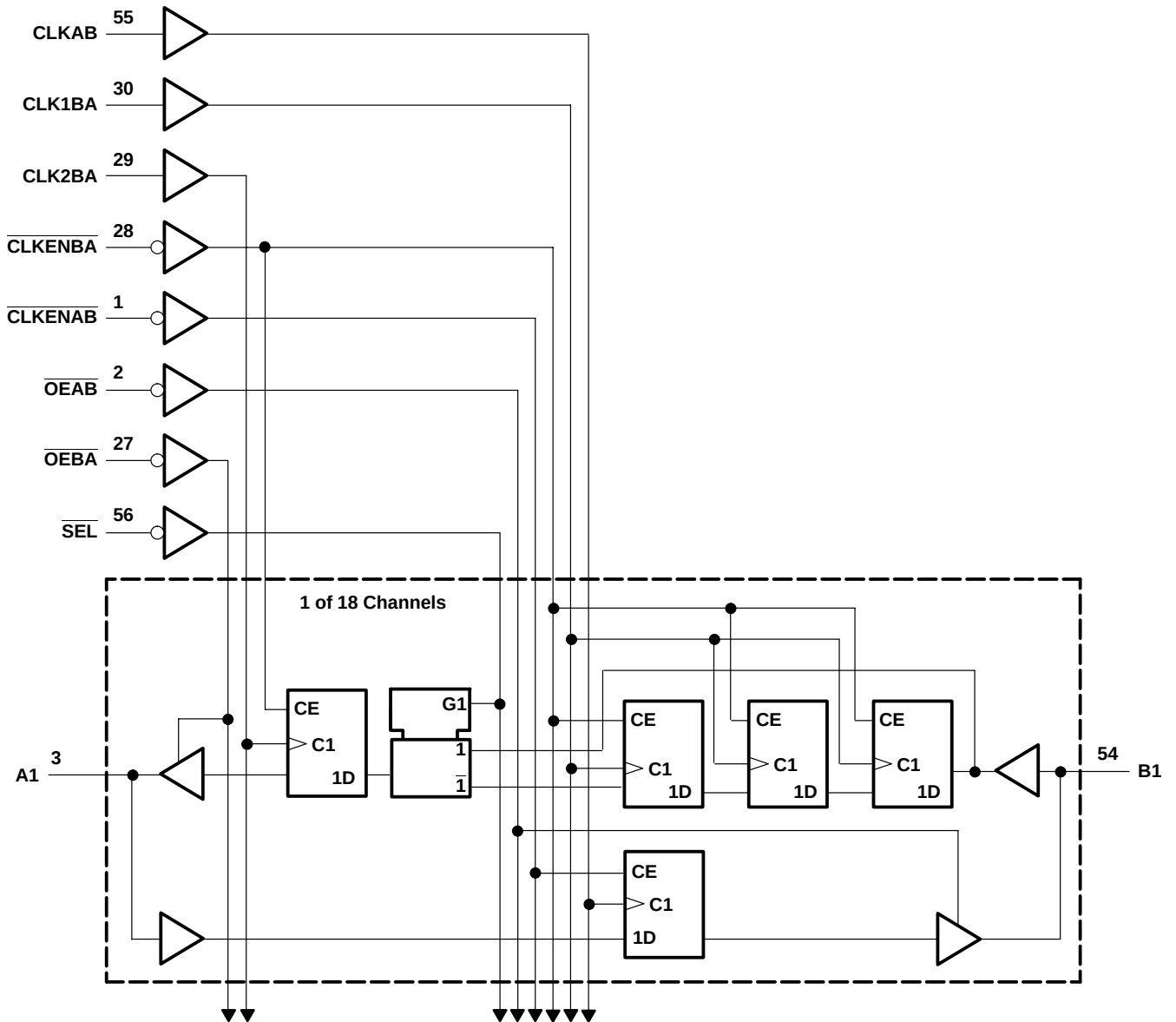
$\dagger$ Output level before the indicated steady-state input conditions were established

$\ddagger$ Three CLK1BA edges and one CLK2BA edge are needed to propagate data from B to A when $\overline{\text{SEL}}$ is low.

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logic diagram (positive logic)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.



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WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current (A port)	V _{CC} = 1.65 V	−4		mA
		V _{CC} = 2.3 V	−12		
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
	High-level output current (B port)	V _{CC} = 1.65 V	−2		
		V _{CC} = 2.3 V	−6		
		V _{CC} = 2.7 V	−8		
		V _{CC} = 3 V	−12		
I _{OL}	Low-level output current (A port)	V _{CC} = 1.65 V	4		mA
		V _{CC} = 2.3 V	12		
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
	Low-level output current (B port)	V _{CC} = 1.65 V	2		
		V _{CC} = 2.3 V	6		
		V _{CC} = 2.7 V	8		
		V _{CC} = 3 V	12		
Δt/Δv	Input transition rise or fall rate			10	ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	A port	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
	B port	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}	A port	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 4 mA	1.65 V	0.45			
		I _{OL} = 6 mA	2.3 V	0.4			
		I _{OL} = 12 mA	2.3 V	0.7			
			2.7 V	0.4			
		I _{OL} = 24 mA	3 V	0.55			
	B port	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V		–25			
		V _I = 0.7 V		45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V		75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]		±500			
I _{OZ} [§]		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3			pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V	7			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.



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18-BIT REGISTERED BUS TRANSCEIVER
WITH 3-STATE OUTPUTS

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency		†		120		125		150		MHz
t _w	Pulse duration, CLK high or low		†		3.2		3.2		3		ns
t _{su}	Setup time	A data before CLKAB↑	†		1.3		1.3		1.3		ns
		B data before CLK2BA↑	†		2.1		1.8		1.7		
		B data before CLK1BA↑	†		1.3		1.2		1.1		
		SEL before CLK2BA↑	†		3.3		3.3		3.3		
		CLKENAB before CLKAB↑	†		2.1		1.9		1.6		
		CLKENBA before CLK1BA↑	†		2.7		2.5		2.1		
		CLKENBA before CLK2BA↑	†		2.7		2.5		2.2		
t _h	Hold time	A data after CLKAB↑	†		0.7		0.4		0.9		ns
		B data after CLK2BA↑	†		0.4		0		0.6		
		B data after CLK1BA↑	†		0.8		0.4		1		
		SEL after CLK2BA↑	†		0		0		0.1		
		CLKENAB after CLKAB↑	†		0.1		0.3		0.3		
		CLKENBA after CLK1BA↑	†		0		0		0.1		
		CLKENBA after CLK2BA↑	†		0		0		0		

† This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 1.8\text{ V}$		$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f_{max}			†		120		125		150		MHz
t_{pd}	CLKAB	B	†		1	5.5	5.4		1	4.7	ns
	CLK2BA	A	†		1	4.5	4.4		1	4.2	
t_{en}	OEBA	A	†		1	6.1	6.1		1	5.1	ns
	OEAB	B	†		1	6.7	6.8		1	5.7	
t_{dis}	OEBA	A	†		1	6.3	5.4		1	4.9	ns
	OEAB	B	†		1	6.3	5.4		1	4.9	

† This information was not available at the time of publication.

operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER			TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
				TYP	TYP	TYP	
C_{pd}	Power dissipation capacitance	Outputs enabled	$C_L = 50\text{ pF}, f = 10\text{ MHz}$	†	160	160	pF
		Outputs disabled		†	160	160	

† This information was not available at the time of publication.

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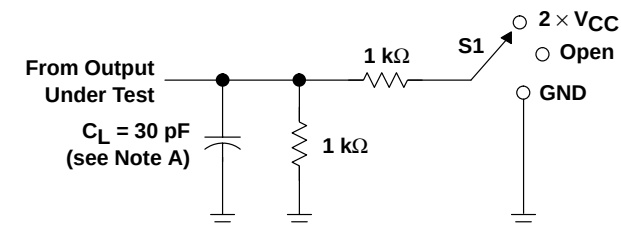
18-BIT REGISTERED BUS TRANSCEIVER

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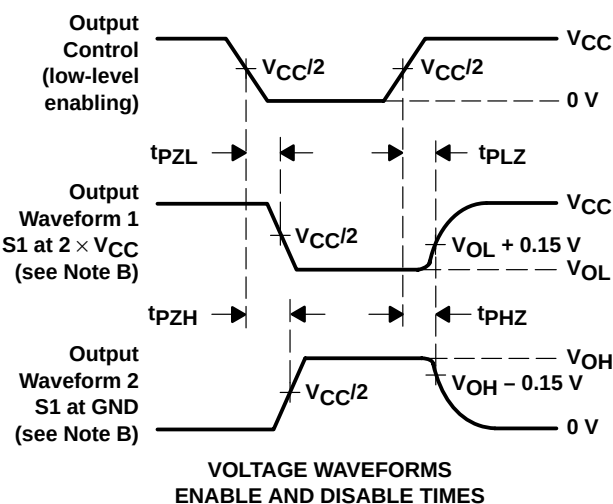
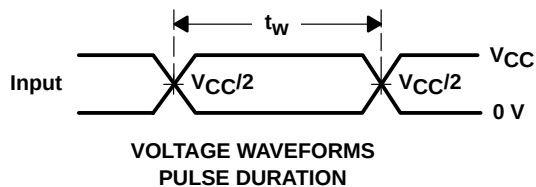
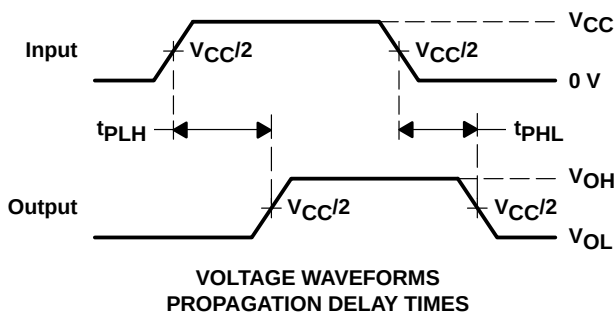
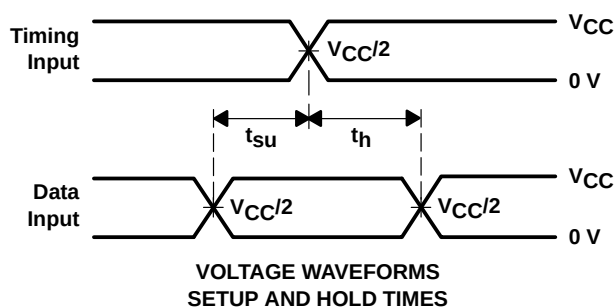
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PHL}	GND

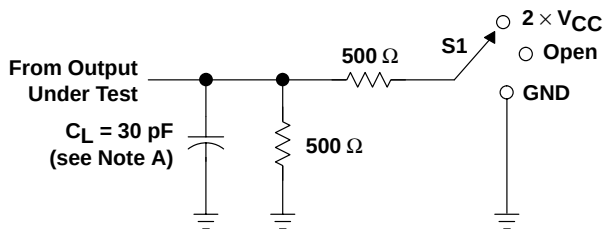


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

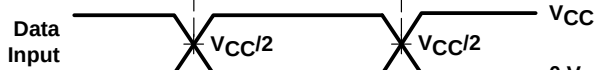
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

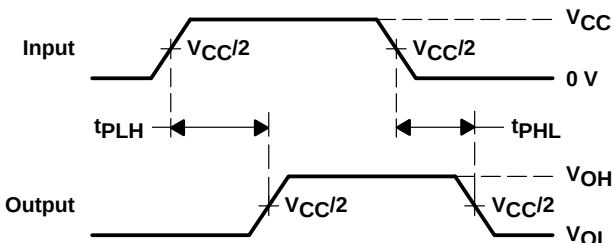


LOAD CIRCUIT

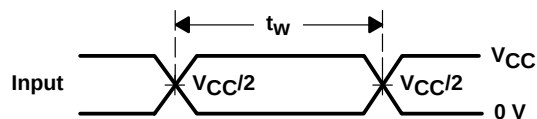
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



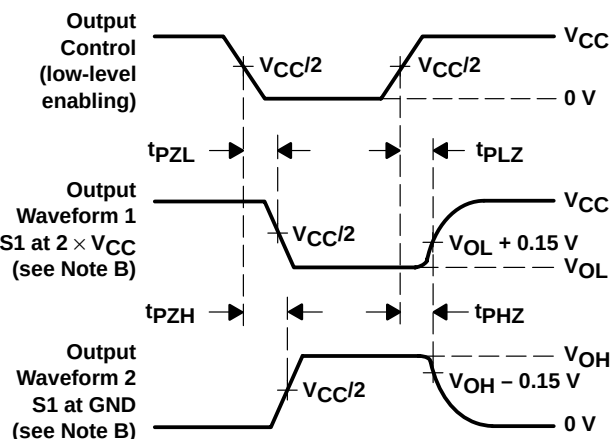
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
D. The outputs are measured one at a time with one transition per measurement.
E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
F. t_{PZL} and t_{PZH} are the same as t_{en} .
G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH162525

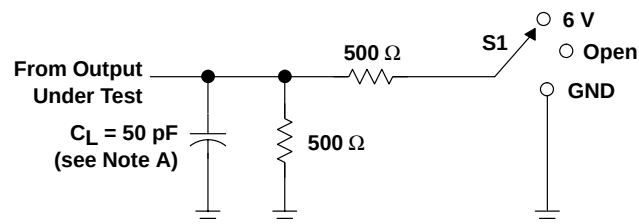
18-BIT REGISTERED BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

SCES058D – NOVEMBER 1995 – REVISED FEBRUARY 1999

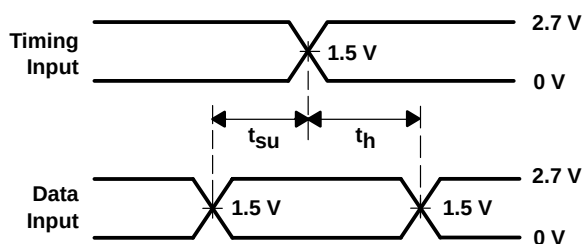
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$

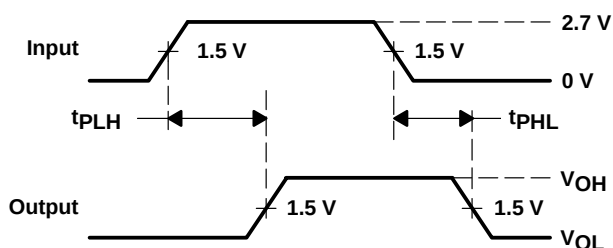


LOAD CIRCUIT

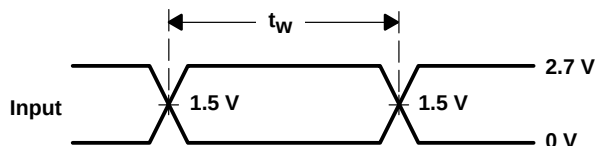
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



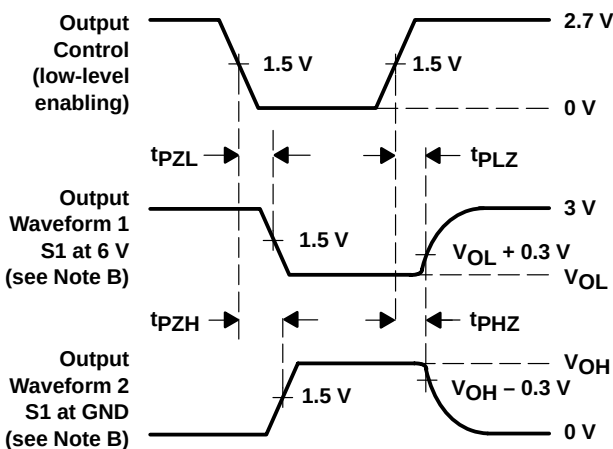
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH162601

18-BIT UNIVERSAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

SCES026F – JULY 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- *UBT™* (Universal Bus Transceiver) Combines D-Type Latches and D-Type Flip-Flops for Operation in Transparent, Latched, Clocked, or Clock-Enabled Mode
- B-Port Outputs Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 18-bit universal bus transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH162601 combines D-type latches and D-type flip-flops to allow data flow in transparent, latched, clocked, and clock-enabled modes.

Data flow in each direction is controlled by output-enable ($\overline{OEAB}$ and $\overline{OEBA}$), latch-enable (LEAB and LEBA), and clock (CLKAB and CLKBA) inputs. The clock can be controlled by the clock-enable ($\overline{CLKENAB}$ and $\overline{CLKENBA}$) inputs. For A-to-B data flow, the device operates in the transparent mode when LEAB is high. When LEAB is low, the A data is latched if CLKAB is held at a high or low logic level. If LEAB is low, the A data is stored in the latch/flip-flop on the low-to-high transition of CLKAB. When $\overline{OEAB}$ is low, the outputs are active. When $\overline{OEAB}$ is high, the outputs are in the high-impedance state.

Data flow for B to A is similar to that of A to B but uses $\overline{OEBA}$, LEBA, CLKBA, and $\overline{CLKENBA}$.

The B-port outputs include equivalent 26-Ω series resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH162601 is characterized for operation from -40°C to 85°C.

DGG OR DL PACKAGE
(TOP VIEW)

$\overline{OEAB}$	1	56	$\overline{CLKENAB}$
LEAB	2	55	CLKAB
A1	3	54	B1
GND	4	53	GND
A2	5	52	B2
A3	6	51	B3
V_{CC}	7	50	V_{CC}
A4	8	49	B4
A5	9	48	B5
A6	10	47	B6
GND	11	46	GND
A7	12	45	B7
A8	13	44	B8
A9	14	43	B9
A10	15	42	B10
A11	16	41	B11
A12	17	40	B12
GND	18	39	GND
A13	19	38	B13
A14	20	37	B14
A15	21	36	B15
V_{CC}	22	35	V_{CC}
A16	23	34	B16
A17	24	33	B17
GND	25	32	GND
A18	26	31	B18
$\overline{OEBA}$	27	30	CLKBA
LEBA	28	29	$\overline{CLKENBA}$

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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SN74ALVCH162601
18-BIT UNIVERSAL BUS TRANSCEIVER
WITH 3-STATE OUTPUTS

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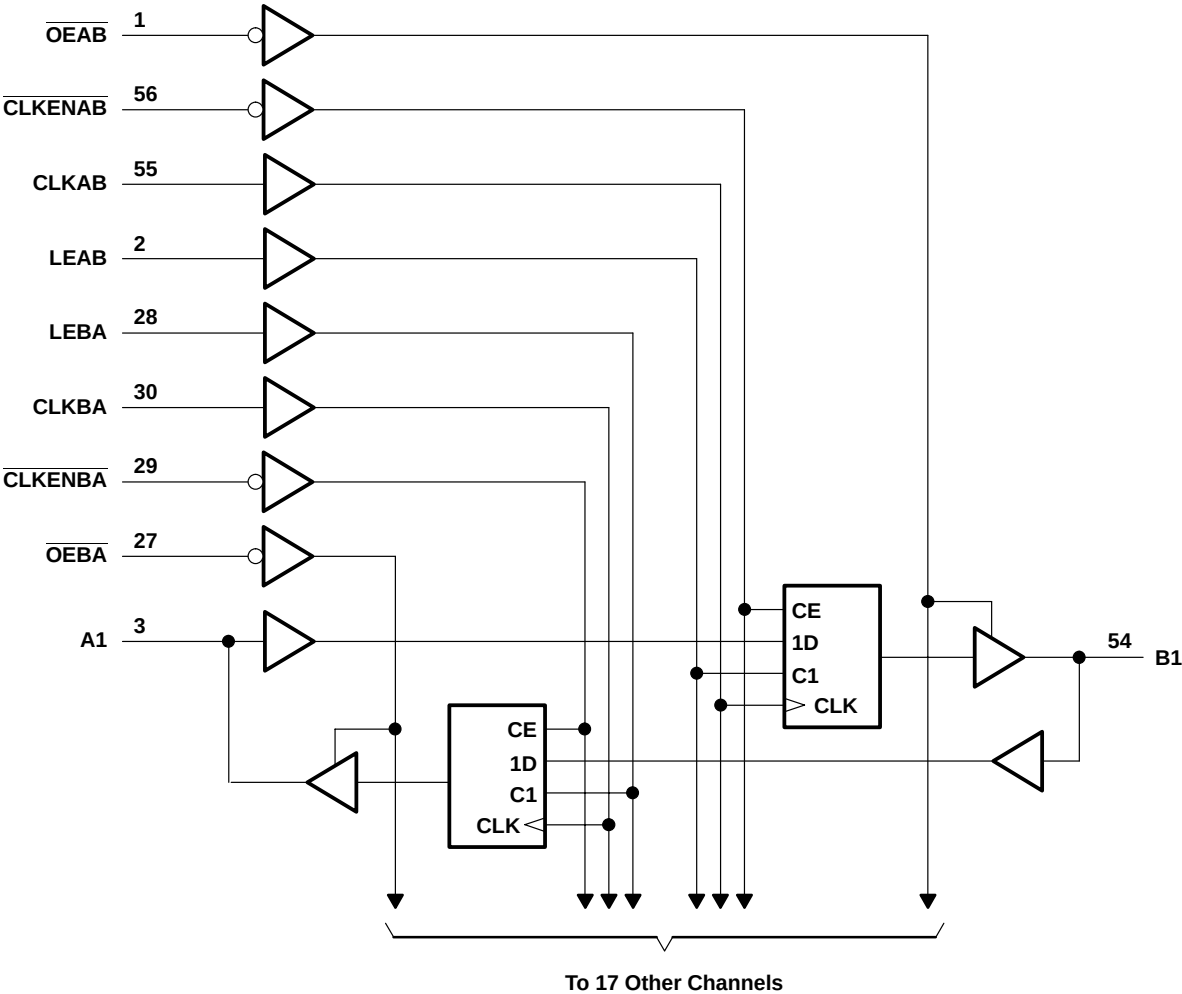
FUNCTION TABLE†

INPUTS					OUTPUT B
CLKENAB	OEAB	LEAB	CLKAB	A	
X	H	X	X	X	Z
X	L	H	X	L	L
X	L	H	X	H	H
H	L	L	X	X	B ₀ ‡
H	L	L	X	X	B ₀ ‡
L	L	L	↑	L	L
L	L	L	↑	H	H
L	L	L	L or H	X	B ₀ ‡

† A-to-B data flow is shown: B-to-A flow is similar but uses OEBA, LEBA, CLKBA, and CLKENBA.

‡ Output level before the indicated steady-state input conditions were established

logic diagram (positive logic)



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18-BIT UNIVERSAL BUS TRANSCEIVER
WITH 3-STATE OUTPUTS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.



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recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V_{CC}	Supply voltage		1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65\text{ V to }1.95\text{ V}$	$0.65 \times V_{CC}$		V
		$V_{CC} = 2.3\text{ V to }2.7\text{ V}$	1.7		
		$V_{CC} = 2.7\text{ V to }3.6\text{ V}$	2		
V_{IL}	Low-level input voltage	$V_{CC} = 1.65\text{ V to }1.95\text{ V}$		$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3\text{ V to }2.7\text{ V}$		0.7	
		$V_{CC} = 2.7\text{ V to }3.6\text{ V}$		0.8	
V_I	Input voltage		0	V_{CC}	V
V_O	Output voltage		0	V_{CC}	V
I_{OH}	High-level output current (A port)	$V_{CC} = 1.65\text{ V}$		–4	mA
		$V_{CC} = 2.3\text{ V}$		–12	
		$V_{CC} = 2.7\text{ V}$		–12	
		$V_{CC} = 3\text{ V}$		–24	
	High-level output current (B port)	$V_{CC} = 1.65\text{ V}$		–2	
		$V_{CC} = 2.3\text{ V}$		–6	
		$V_{CC} = 2.7\text{ V}$		–8	
		$V_{CC} = 3\text{ V}$		–12	
I_{OL}	Low-level output current (A port)	$V_{CC} = 1.65\text{ V}$		4	mA
		$V_{CC} = 2.3\text{ V}$		12	
		$V_{CC} = 2.7\text{ V}$		12	
		$V_{CC} = 3\text{ V}$		24	
	Low-level output current (B port)	$V_{CC} = 1.65\text{ V}$		2	
		$V_{CC} = 2.3\text{ V}$		6	
		$V_{CC} = 2.7\text{ V}$		8	
		$V_{CC} = 3\text{ V}$		12	
$\Delta t/\Delta v$	Input transition rise or fall rate			10	ns/V
T_A	Operating free-air temperature		–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



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18-BIT UNIVERSAL BUS TRANSCEIVER
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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	A port	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –4 mA	1.65 V	1.2			
		I _{OH} = –6 mA	2.3 V	2			
		I _{OH} = –12 mA	2.3 V	1.7			
			2.7 V	2.2			
			3 V	2.4			
		I _{OH} = –24 mA	3 V	2			
	B port	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
			2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}	A port	I _{OL} = 100 µA	1.65 V to 3.6 V			0.2	V
		I _{OL} = 4 mA	1.65 V			0.45	
		I _{OL} = 6 mA	2.3 V			0.4	
		I _{OL} = 12 mA	2.3 V			0.7	
			2.7 V			0.4	
		I _{OL} = 24 mA	3 V			0.55	
	B port	I _{OL} = 100 µA	1.65 V to 3.6 V			0.2	
		I _{OL} = 2 mA	1.65 V			0.45	
		I _{OL} = 4 mA	2.3 V			0.4	
		I _{OL} = 6 mA	2.3 V			0.55	
			3 V			0.55	
		I _{OL} = 8 mA	2.7 V			0.6	
		I _{OL} = 12 mA	3 V			0.8	
I _I		V _I = V _{CC} or GND	3.6 V			±5	µA
I _{I(hold)}		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V		–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V		–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V		–75			
		V _I = 0 to 3.6 V [‡]	3.6 V			±500	
I _{OZ} [§]		V _O = V _{CC} or GND	3.6 V			±10	µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V			40	µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V			750	µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V		4		pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V		8		pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.



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18-BIT UNIVERSAL BUS TRANSCEIVER

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

				V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT	
				MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
f _{clock}	Clock frequency			†		140		150		150		MHz	
t _w	Pulse duration	LE high		†		3.3		3.3		3.3		ns	
		CLK high or low		†		3.3		3.3		3.3			
t _{su}	Setup time	Data before CLK↑		†		2.3		2.4		2.1		ns	
		Data before LE↓	CLK high		†		2		1.6		1.6		
			CLK low		†		1.3		1.2		1.1		
		CLKEN before CLK↑		†		2		2		1.7			
t _h	Hold time	Data after CLK↑		†		0.7		0.7		0.8		ns	
		Data after LE↓	CLK high		†		1.3		1.6		1.4		
			CLK low		†		1.7		2		1.7		
		CLKEN after CLK↑		†		0.3		0.5		0.6			

† This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 1.8\text{ V}$		$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f_{max}			†		140		150		150		MHz
t_{pd}	A	B	†		1.3	4.8	5.2		1.6	4.5	ns
	B	A	†		1	4.3	4.6		1	4.1	
	LEAB	B	†		1	5.5	5.9		1.5	5.1	
	LEBA	A	†		1	5	5.3		1	4.7	
	CLKAB	B	†		1.5	6.1	6.3		1.6	5.5	
	CLKBA	A	†		1.3	5.6	5.8		1.4	5	
t_{en}	$\overline{OEAB}$	B	†		1.6	6.1	6.7		1.6	5.7	ns
t_{dis}	$\overline{OEAB}$	B	†		1.8	5.7	5.3		1.8	4.8	ns
t_{en}	$\overline{OEBA}$	A	†		1.1	5.5	6.1		1.1	5.2	ns
t_{dis}	$\overline{OEBA}$	A	†		1.3	5.2	4.8		1.6	4.4	ns

† This information was not available at the time of publication.

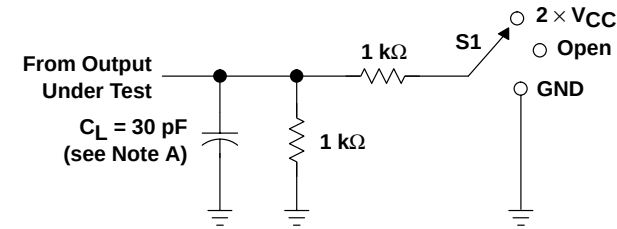
operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER			TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
				TYP	TYP	TYP	
C_{pd}	Power dissipation capacitance	Outputs enabled	$C_L = 50\text{ pF}, f = 10\text{ MHz}$	†	41	50	pF
		Outputs disabled		†	6	6	

† This information was not available at the time of publication.

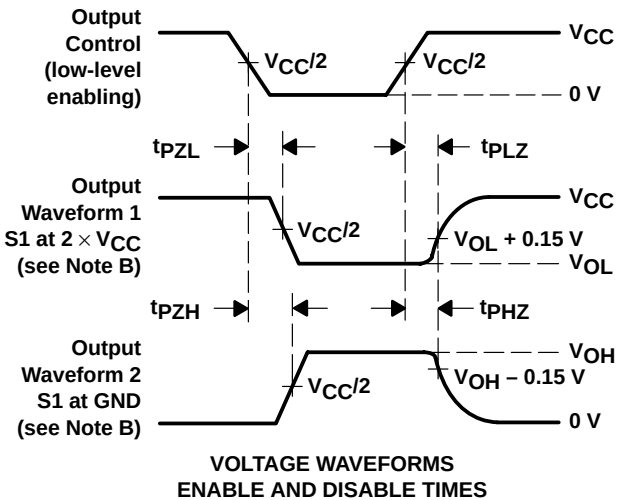
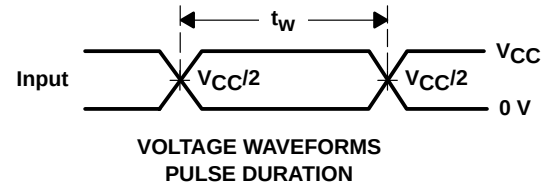
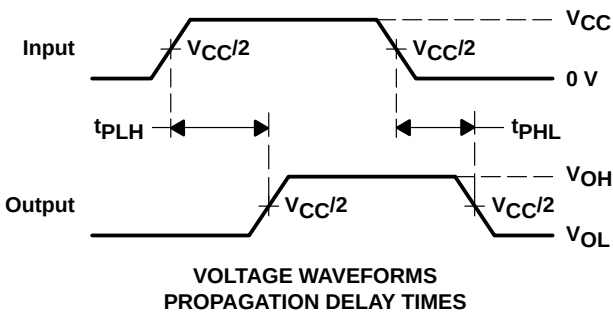
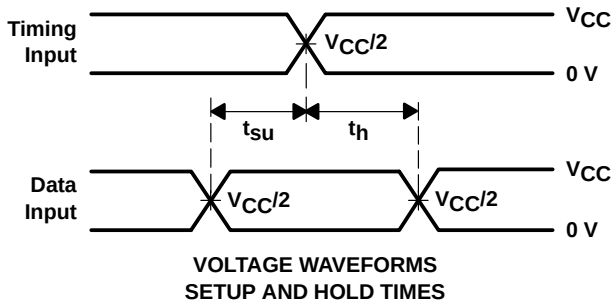


PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH162601

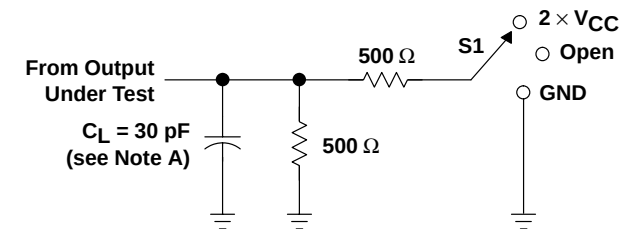
18-BIT UNIVERSAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

SCES026F – JULY 1995 – REVISED FEBRUARY 1999

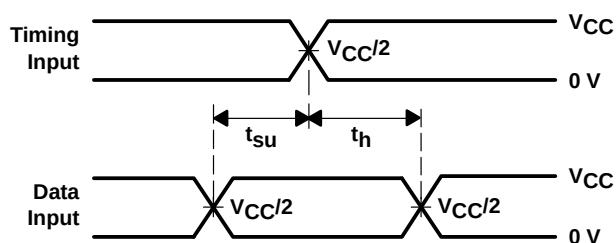
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

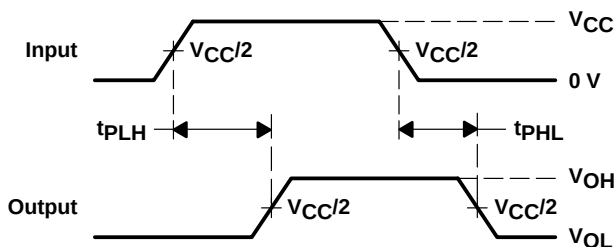


LOAD CIRCUIT

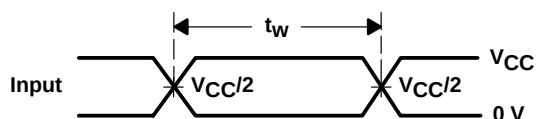
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



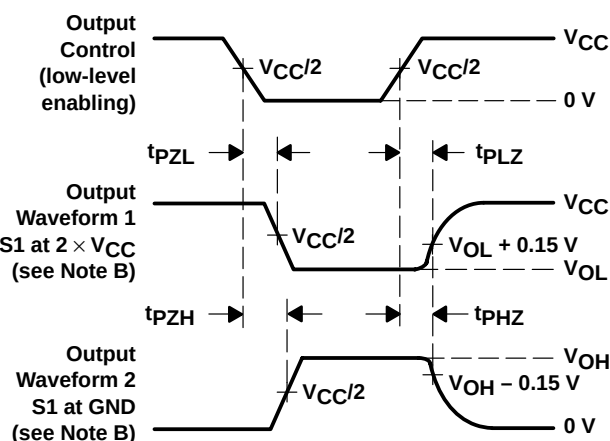
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



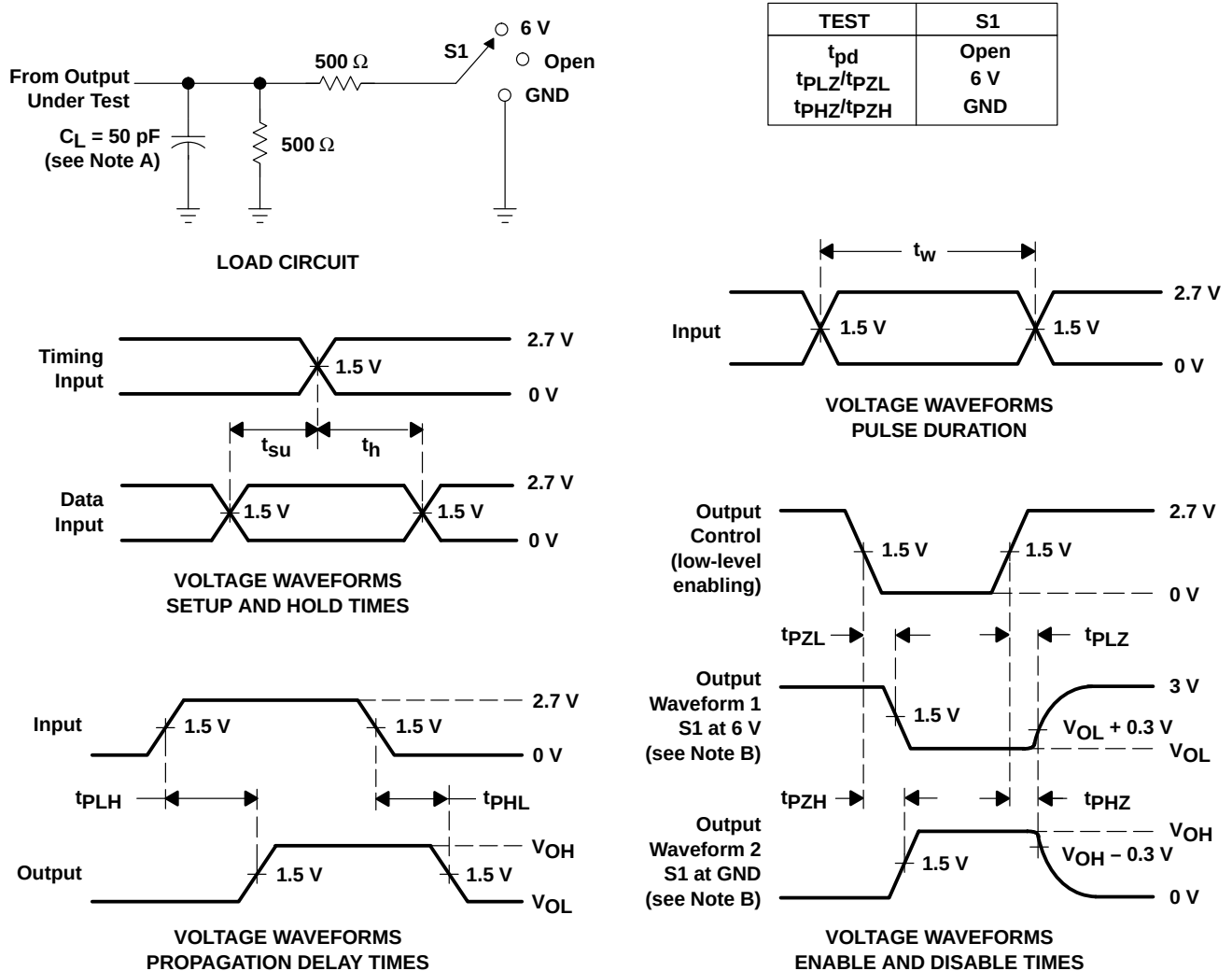
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
D. The outputs are measured one at a time with one transition per measurement.
E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
F. t_{PZL} and t_{PZH} are the same as t_{en} .
G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCHR16601

18-BIT UNIVERSAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

SCES123F – SEPTEMBER 1997 – REVISED MARCH 1999

- **Member of the Texas Instruments Widebus™ Family**
- **EPIC™ (Enhanced-Performance Implanted CMOS) Submicron Process**
- **UBT™ (Universal Bus Transceiver) Combines D-Type Latches and D-Type Flip-Flops for Operation in Transparent, Latched, Clocked, or Clock-Enabled Mode**
- **Output Ports Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required**
- **ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)**
- **Latch-Up Performance Exceeds 250 mA Per JESD 17**
- **Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors**
- **Package Options Include Plastic Thin Shrink Small-Outline (DGG), Thin Very Small-Outline (DGV), and 300-mil Shrink Small-Outline (DL) Packages**

NOTE: For order entry:

The DGG package is abbreviated to G,
the DGV package is abbreviated to V, and
the DL package is abbreviated to L.

description

This 18-bit universal bus transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCHR16601 combines D-type latches and D-type flip-flops to allow data flow in transparent, latched, clocked, and clock-enabled modes.

Data flow in each direction is controlled by output-enable ($\overline{OEAB}$ and $\overline{OEBA}$), latch-enable (LEAB and LEBA), and clock (CLKAB and CLKBA) inputs. The clock can be controlled by the clock-enable ($\overline{CLKENAB}$ and $\overline{CLKENBA}$) inputs. For A-to-B data flow, the device operates in the transparent mode when LEAB is high. When LEAB is low, the A data is latched if CLKAB is held at a high or low logic level. If LEAB is low, the A data is stored in the latch/flip-flop on the low-to-high transition of CLKAB. When $\overline{OEAB}$ is low, the outputs are active. When $\overline{OEAB}$ is high, the outputs are in the high-impedance state.

Data flow for B to A is similar to that of A to B but uses $\overline{OEBA}$, LEBA, CLKBA, and $\overline{CLKENBA}$.

The outputs include equivalent 26-Ω series resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

DGG, DGV, OR DL PACKAGE
(TOP VIEW)

$\overline{OEAB}$	1	56	$\overline{CLKENAB}$
LEAB	2	55	CLKAB
A1	3	54	B1
GND	4	53	GND
A2	5	52	B2
A3	6	51	B3
V_{CC}	7	50	V_{CC}
A4	8	49	B4
A5	9	48	B5
A6	10	47	B6
GND	11	46	GND
A7	12	45	B7
A8	13	44	B8
A9	14	43	B9
A10	15	42	B10
A11	16	41	B11
A12	17	40	B12
GND	18	39	GND
A13	19	38	B13
A14	20	37	B14
A15	21	36	B15
V_{CC}	22	35	V_{CC}
A16	23	34	B16
A17	24	33	B17
GND	25	32	GND
A18	26	31	B18
$\overline{OEBA}$	27	30	CLKBA
LEBA	28	29	$\overline{CLKENBA}$

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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SN74ALVCHR16601
18-BIT UNIVERSAL BUS TRANSCEIVER
WITH 3-STATE OUTPUTS

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description (continued)

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCHR16601 is characterized for operation from –40°C to 85°C.

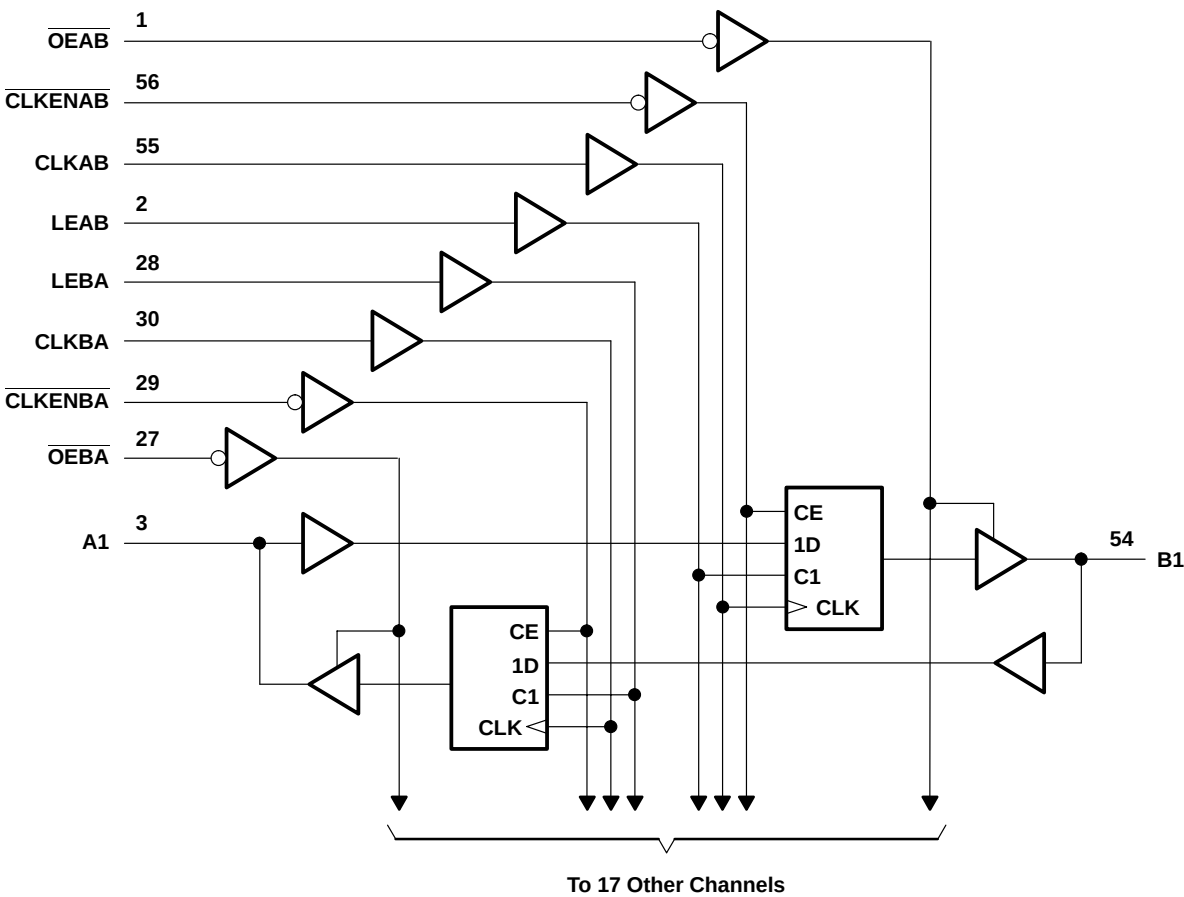
FUNCTION TABLE†

INPUTS					OUTPUT B
CLKENAB	OEAB	LEAB	CLKAB	A	
X	H	X	X	X	Z
X	L	H	X	L	L
X	L	H	X	H	H
H	L	L	X	X	B ₀ ‡
L	L	L	↑	L	L
L	L	L	↑	H	H
L	L	L	L or H	X	B ₀ ‡

† A-to-B data flow is shown: B-to-A flow is similar but uses OEBA, LEBA, CLKBA, and CLKENBA.

‡ Output level before the indicated steady-state input conditions were established

logic diagram (positive logic)



Supply voltage range, V_{CC}	−0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	−0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	−0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	−0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	−50 mA
Output clamp current, I_{OK} ($V_O < 0$)	−50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DGV package	86°C/W
DL package	74°C/W

NOTES:

1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−2		mA
		V _{CC} = 2.3 V	−6		
		V _{CC} = 2.7 V	−8		
		V _{CC} = 3 V	−12		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	2		mA
		V _{CC} = 2.3 V	6		
		V _{CC} = 2.7 V	8		
		V _{CC} = 3 V	12		
Δt/Δv	Input transition rise or fall rate		10		ns/V
T _A	Operating free-air temperature		−40	85	°C



**TEXAS
INSTRUMENTS**

SN74ALVCHR16601

18-BIT UNIVERSAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

SCES123F – SEPTEMBER 1997 – REVISED MARCH 1999

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} – 0.2			V
	I _{OH} = –2 mA	1.65 V	1.2			
	I _{OH} = –4 mA	2.3 V	1.9			
	I _{OH} = –6 mA	2.3 V	1.7			
		3 V	2.4			
	I _{OH} = –8 mA	2.7 V	2			
	I _{OH} = –12 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 2 mA	1.65 V	0.45			
	I _{OL} = 4 mA	2.3 V	0.4			
	I _{OL} = 6 mA	2.3 V	0.55			
		3 V	0.55			
	I _{OL} = 8 mA	2.7 V	0.6			
	I _{OL} = 12 mA	3 V	0.8			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V		–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V		–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V		–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ} [§]	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V		4	pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V		8	pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.



SN74ALVCHR16601
18-BIT UNIVERSAL BUS TRANSCEIVER
WITH 3-STATE OUTPUTS

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

				V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT	
				MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
f _{clock}	Clock frequency			†		150		150		150		MHz	
t _w	Pulse duration	LE high		†		3.3		3.3		3.3		ns	
		CLK high or low		†		3.3		3.3		3.3			
t _{su}	Setup time	Data before CLK↑		†		2.3		2.4		2.1		ns	
		Data before LE↓	CLK high		†		2		1.6		1.6		
			CLK low		†		1.3		1.2		1.1		
		CLKEN before CLK↑		†		2		2		1.7			
t _h	Hold time	Data after CLK↑		†		0.7		0.7		0.8		ns	
		Data after LE↓	CLK high		†		1.3		1.6		1.4		
			CLK low		†		1.7		2		1.7		
		CLKEN after CLK↑		†		0.3		0.5		0.6			

† This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 1.8\text{ V}$		$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f_{max}			†		150		150		150		MHz
t_{pd}	A or B	B or A	†		1	4.8	5.1		1	4.4	ns
	LEAB or LEBA		†		1	5.5	5.8		1	5.1	
	CLKAB or CLKBA		†		1.2	5.9	6.3		1.4	5.4	
t_{en}	$\overline{\text{OEAB}}$ or $\overline{\text{OEBA}}$	B or A	†		1.1	6.3	6.6		1.1	5.6	ns
t_{dis}	$\overline{\text{OEAB}}$ or $\overline{\text{OEBA}}$	B or A	†		1	4.2	5.1		1.6	4.7	ns

† This information was not available at the time of publication.

operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER			TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
				TYP	TYP	TYP	
C_{pd}	Power dissipation capacitance	Outputs enabled	$C_L = 0$, $f = 10\text{ MHz}$	†	56	63	pF
		Outputs disabled		†	12	13	

† This information was not available at the time of publication.

SN74ALVCHR16601

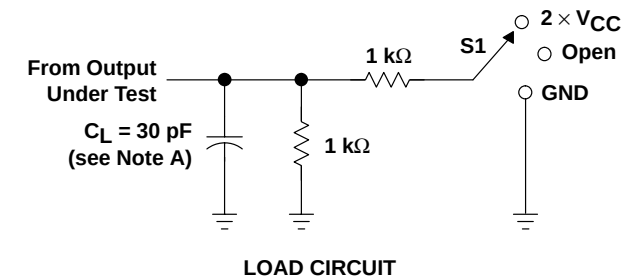
18-BIT UNIVERSAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

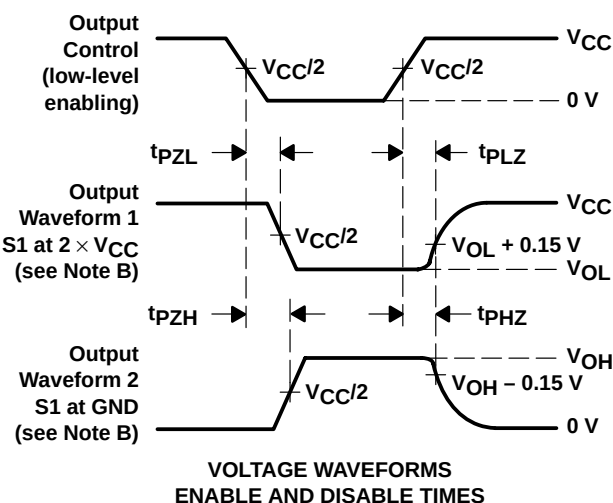
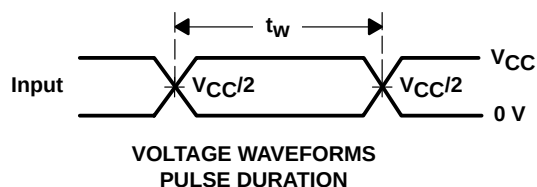
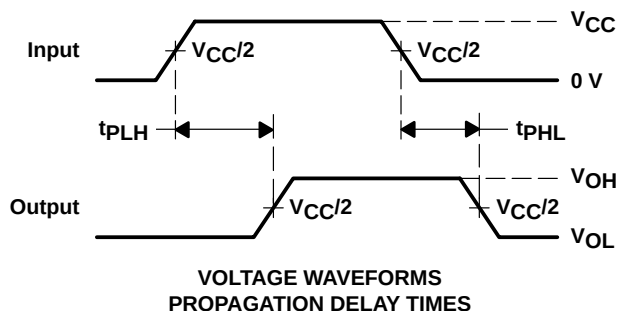
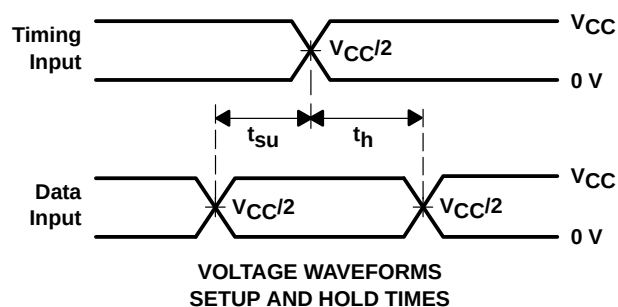
SCES123F – SEPTEMBER 1997 – REVISED MARCH 1999

PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND

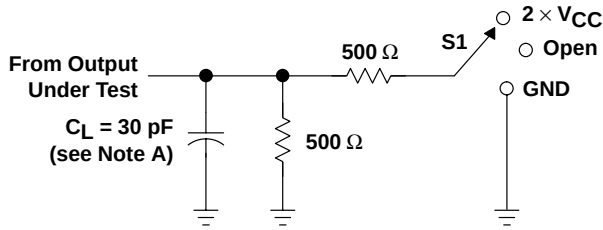


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

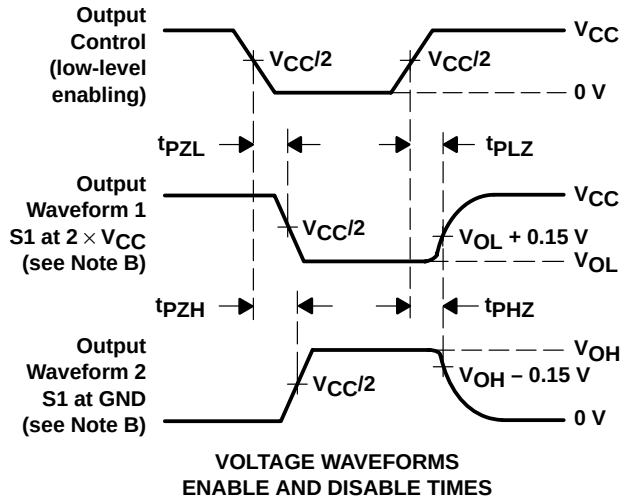
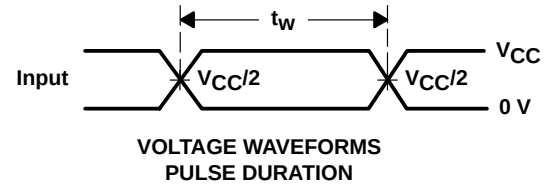
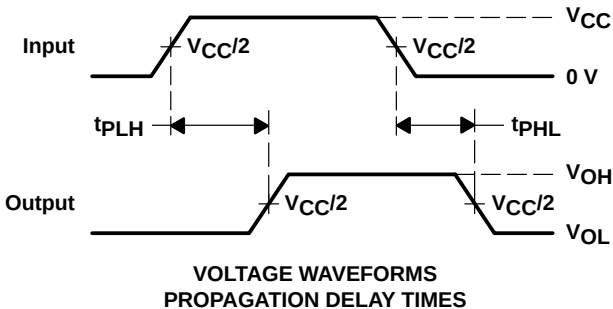
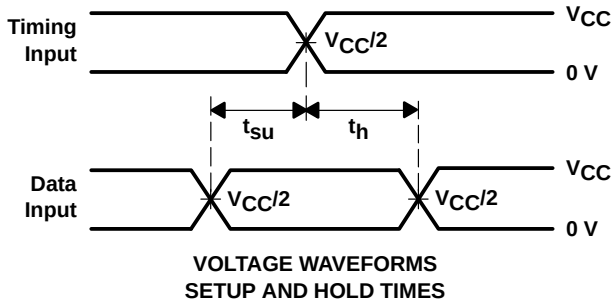
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
D. The outputs are measured one at a time with one transition per measurement.
E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
F. t_{PZL} and t_{PZH} are the same as t_{en} .
G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCHR16601

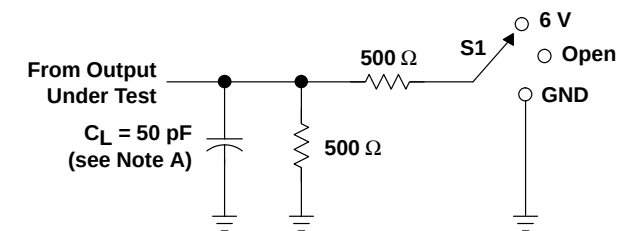
18-BIT UNIVERSAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

SCES123F – SEPTEMBER 1997 – REVISED MARCH 1999

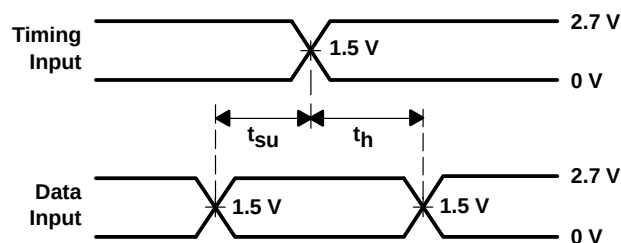
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$

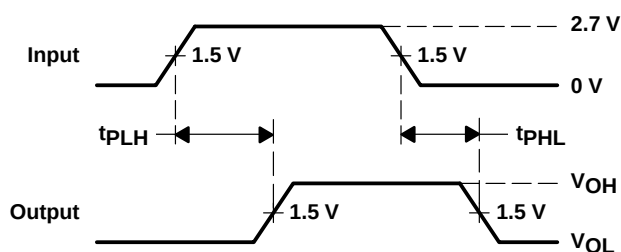


LOAD CIRCUIT

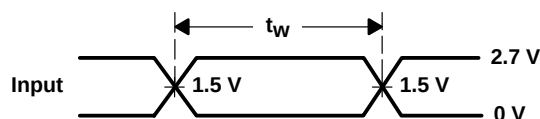
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



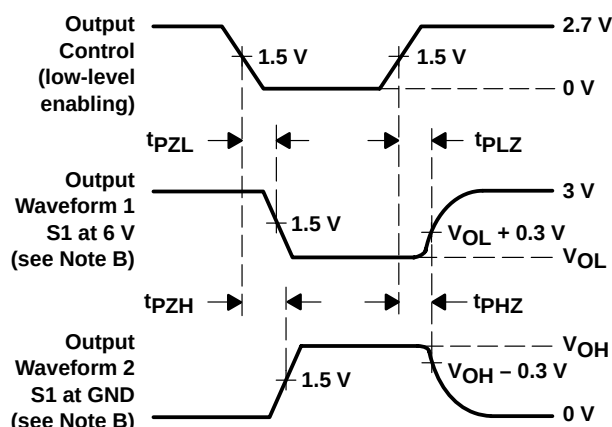
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCHR16269A 12-BIT TO 24-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

SCES050K – AUGUST 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- All Outputs Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Package Options Include Plastic Thin Shrink Small-Outline (DGG), Thin Very Small-Outline (DGV), and 300-mil Shrink Small-Outline (DL) Packages

NOTE: For order entry:
The DGG package is abbreviated to G, and
the DGV package is abbreviated to V.

description

This 12-bit to 24-bit registered bus exchanger is designed for 1.65-V to 3.6-V V_{CC} operation.

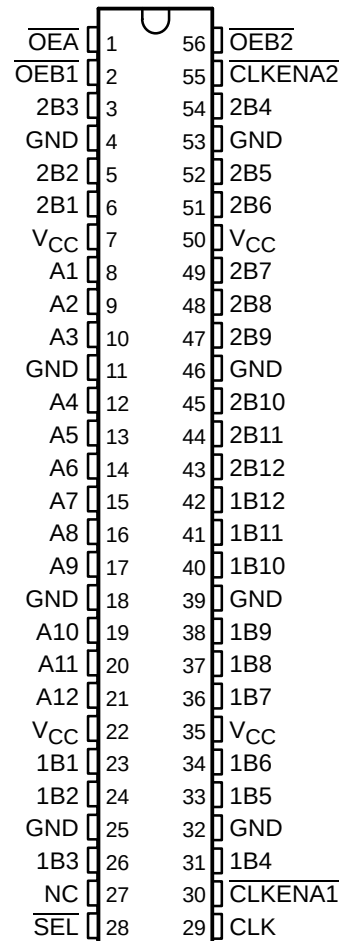
The SN74ALVCHR16269A is used in applications in which two ports must be multiplexed onto, or demultiplexed from, a single port. It is particularly suitable as an interface between synchronous DRAMs and high-speed microprocessors.

Data is stored in the internal B-port registers on the low-to-high transition of the clock (CLK) input when the appropriate clock-enable ($\overline{CLKENA}$) inputs are low. Proper control of these inputs allows two sequential 12-bit words to be presented as a 24-bit word on the B port. For data transfer in the B-to-A direction, a single storage register is provided. The select ($\overline{SEL}$) line selects 1B or 2B data for the A outputs. The register on the A output permits the fastest possible data transfer, thus extending the period during which the data is valid on the bus. The control terminals are registered so that all transactions are synchronous with CLK. Data flow is controlled by the active-low output enables ($\overline{OEA}$, $\overline{OEB1}$, and $\overline{OEB2}$).

To ensure the high-impedance state during power up or power down, a clock pulse should be applied as soon as possible and $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver. Due to $\overline{OE}$ being routed through a register, the active state of the outputs cannot be determined prior to the arrival of the first clock pulse.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

DGG, DGV, OR DL PACKAGE
(TOP VIEW)



NC – No internal connection

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SN74ALVCHR16269A
12-BIT TO 24-BIT REGISTERED BUS EXCHANGER
WITH 3-STATE OUTPUTS

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description (continued)

All outputs are designed to sink up to 12 mA and include equivalent 26-Ω resistors to reduce overshoot and undershoot.

The SN74ALVCHR16269A is characterized for operation from –40°C to 85°C.

Function Tables

OUTPUT ENABLE

INPUTS			OUTPUTS	
CLK	OEA	OEB	A	1B, 2B
↑	H	H	Z	Z
↑	H	L	Z	Active
↑	L	H	Active	Z
↑	L	L	Active	Active

A-TO-B STORAGE
(OEB = L)

INPUTS				OUTPUTS	
CLKENA1	CLKENA2	CLK	A	1B	2B
L	H	↑	L	L	2B ₀ [†]
L	H	↑	H	H	2B ₀ [†]
L	L	↑	L	L	L
L	L	↑	H	H	H
H	L	↑	L	1B ₀ [†]	L
H	L	↑	H	1B ₀ [†]	H
H	H	X	X	1B ₀ [†]	2B ₀ [†]

† Output level before the indicated steady-state input conditions were established

B-TO-A STORAGE
(OEA = L)

INPUTS				OUTPUT A
CLK	SEL	1B	2B	
X	H	X	X	A ₀ [†]
X	L	X	X	A ₀ [†]
↑	H	L	X	L
↑	H	H	X	H
↑	L	X	L	L
↑	L	X	H	H

† Output level before the indicated steady-state input conditions were established

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DGV package	86°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–2	mA
		$V_{CC} = 2.3$ V	–6	
		$V_{CC} = 2.7$ V	–8	
		$V_{CC} = 3$ V	–12	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	2	mA
		$V_{CC} = 2.3$ V	6	
		$V_{CC} = 2.7$ V	8	
		$V_{CC} = 3$ V	12	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



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WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V			±5	µA
I _I (hold)		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V		–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V		–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V		–75			
		V _I = 0 to 3.6 V [‡]	3.6 V			±500	
I _{OZ} [§]		V _O = V _{CC} or GND	3.6 V			±10	µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V			40	µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V			750	µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V			5	pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V			8.5	pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.



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12-BIT TO 24-BIT REGISTERED BUS EXCHANGER

WITH 3-STATE OUTPUTS

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency	†		95		115		135		MHz
t _w	Pulse duration, CLK high or low	†		5.2		4.3		3.3		ns
t _{su}	Setup time	A data before CLK↑		†		1.4		1.4		ns
		B data before CLK↑		†		1.6		1.5		
		SEL before CLK↑		†		0.8		1.1		
		CLKENA1 or CLKENA2 before CLK↑		†		0.8		1		
		OE before CLK↑		†		1.7		1.6		
t _h	Hold time	A data after CLK↑		†		0.9		0.9		ns
		B data after CLK↑		†		0.8		0.6		
		SEL after CLK↑		†		1.1		0.8		
		CLKENA1 or CLKENA2 after CLK↑		†		1.4		1		
		OE after CLK↑		†		0.9		0.8		

† This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		95		115		135		MHz
t _{pd}	CLK	B	†		2.3	7.7	6.9		2.2	5.8	ns
		A	†		1.9	6.4	5.8		2	5.2	
t _{en}	CLK	B	†		2.5	7.7	6.9		2.3	5.8	ns
		A	†		2.2	6.7	6		2.1	5.3	
t _{dis}	CLK	B	†		3.3	8.1	6.7		2.4	6	ns
		A	†		2.7	8	6.2		2.1	6	

† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	All outputs enabled	C _L = 0, f = 10 MHz	†	142	172	pF
		All outputs disabled		†	115	129	

† This information was not available at the time of publication.



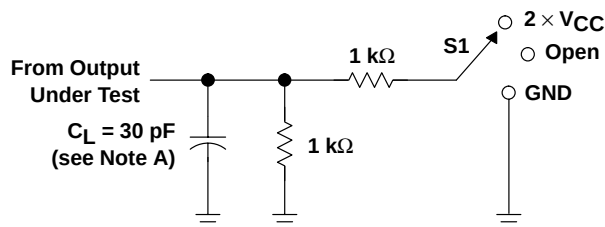
SN74ALVCHR16269A

12-BIT TO 24-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

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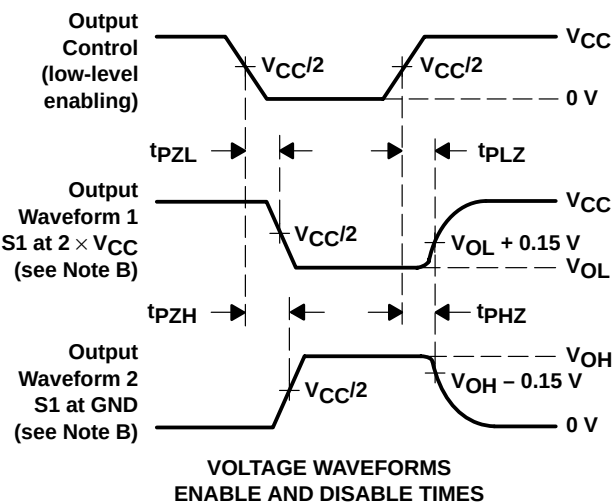
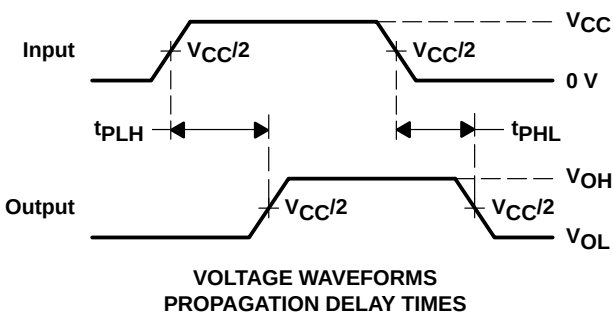
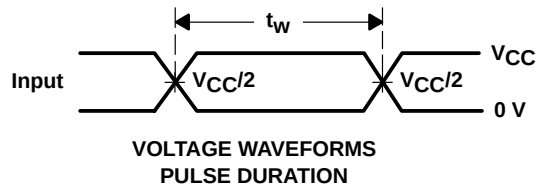
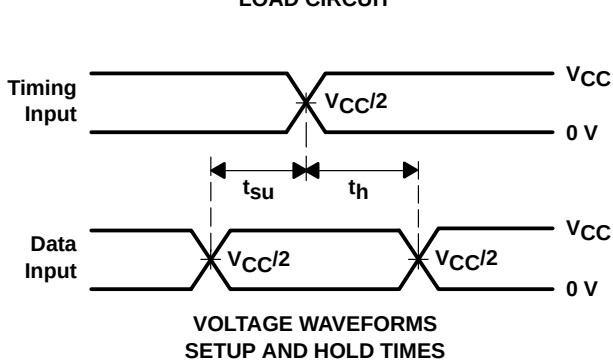
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCHR16269A

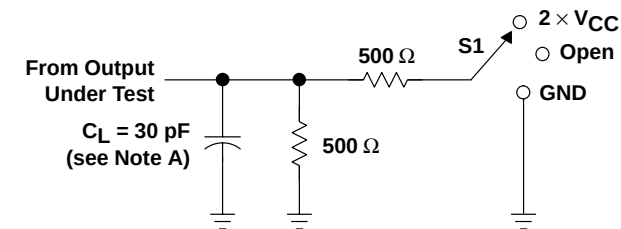
12-BIT TO 24-BIT REGISTERED BUS EXCHANGER

WITH 3-STATE OUTPUTS

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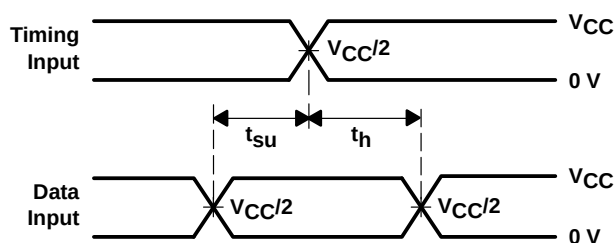
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

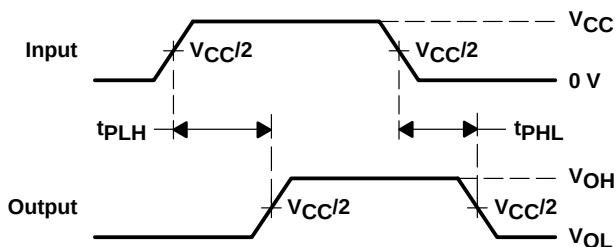


LOAD CIRCUIT

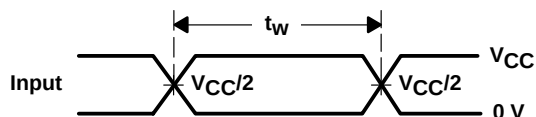
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



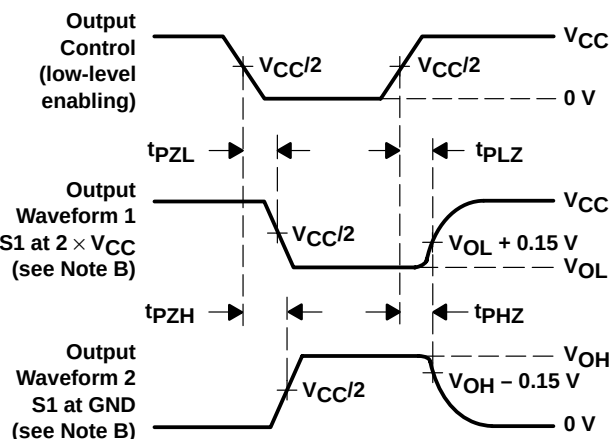
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

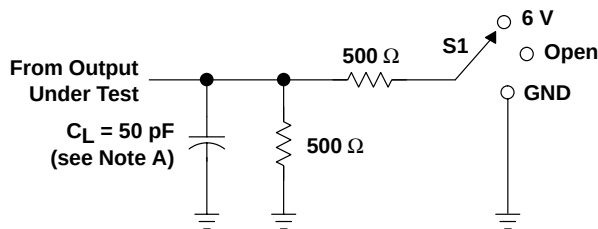
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12-BIT TO 24-BIT REGISTERED BUS EXCHANGER WITH 3-STATE OUTPUTS

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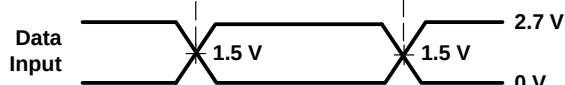
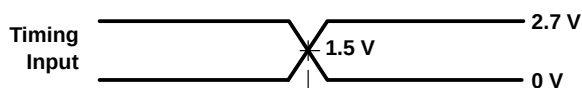
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

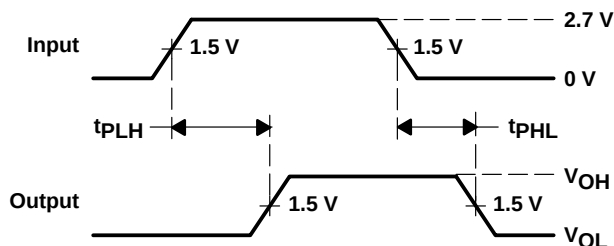


LOAD CIRCUIT

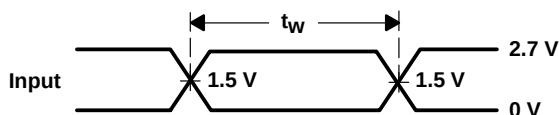
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



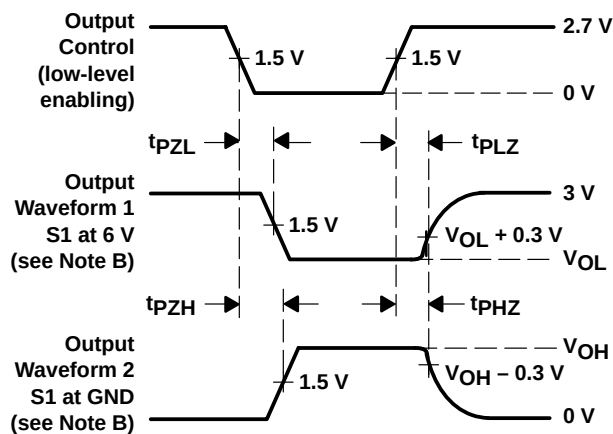
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH162721

3.3-V 20-BIT FLIP-FLOP

WITH 3-STATE OUTPUTS

SCES055D – DECEMBER 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- Output Ports Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 20-bit flip-flop is designed for low-voltage 1.65-V to 3.6-V V_{CC} operation.

The 20 flip-flops of the SN74ALVCH162721 are edge-triggered D-type flip-flops with qualified clock storage. On the positive transition of the clock (CLK) input, the device provides true data at the Q outputs if the clock-enable ($\overline{CLKEN}$) input is low. If $\overline{CLKEN}$ is high, no data is stored.

A buffered output-enable ($\overline{OE}$) input places the 20 outputs in either a normal logic state (high or low level) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components. $\overline{OE}$ does not affect the internal operation of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

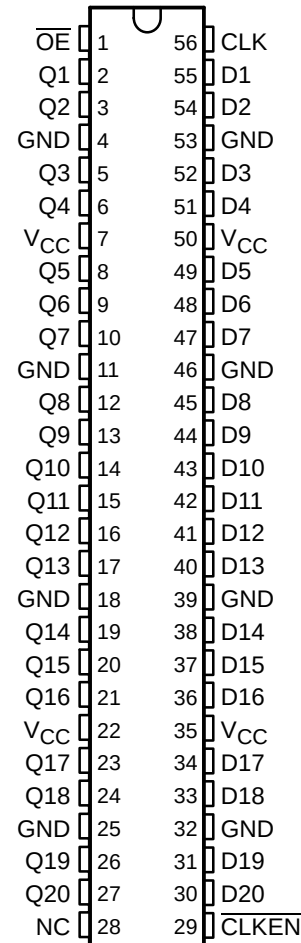
To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The outputs, which are designed to sink up to 12 mA, include equivalent 26-Ω resistors to reduce overshoot and undershoot.

The SN74ALVCH162721 is characterized for operation from –40°C to 85°C.

DGG OR DL PACKAGE (TOP VIEW)



NC – No internal connection

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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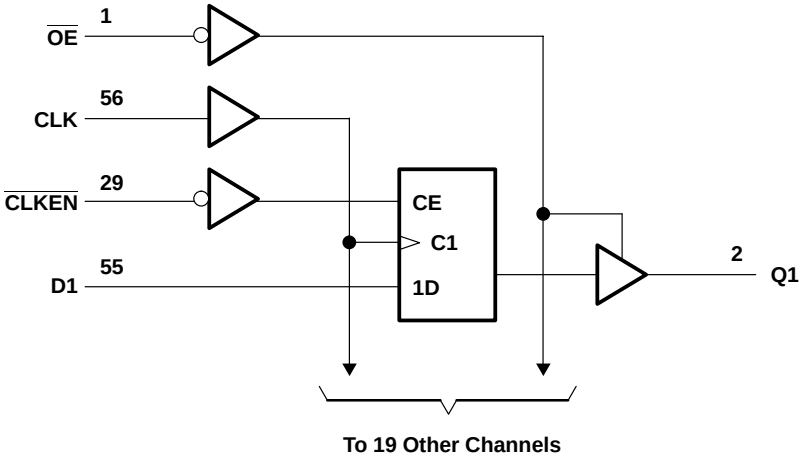
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FUNCTION TABLE

(each flip-flop)

INPUTS				OUTPUT
OE	CLKEN	CLK	D	Q
L	H	X	X	Q ₀
L	L	↑	H	H
L	L	↑	L	L
L	L	L or H	X	Q ₀
H	X	X	X	Z

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC}	–0.5 V to 4.6 V
Input voltage range, V _I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V _O (see Notes 1 and 2)	–0.5 V to V _{CC} + 0.5 V
Input clamp current, I _{IK} (V _I < 0)	–50 mA
Output clamp current, I _{OK} (V _O < 0)	–50 mA
Continuous output current, I _O	±50 mA
Continuous current through each V _{CC} or GND	±100 mA
Package thermal impedance, θ _{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
- The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 - This value is limited to 4.6 V maximum.
 - The package thermal impedance is calculated in accordance with JESD 51.

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3.3-V 20-BIT FLIP-FLOP
WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−2		mA
		V _{CC} = 2.3 V	−6		
		V _{CC} = 2.7 V	−8		
		V _{CC} = 3 V	−12		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	2		mA
		V _{CC} = 2.3 V	6		
		V _{CC} = 2.7 V	8		
		V _{CC} = 3 V	12		
Δt/Δv	Input transition rise or fall rate		10		ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} – 0.2			V
	I _{OH} = –2 mA	1.65 V	1.2			
	I _{OH} = –4 mA	2.3 V	1.9			
	I _{OH} = –6 mA	2.3 V	1.7			
		3 V	2.4			
	I _{OH} = –8 mA	2.7 V	2			
	I _{OH} = –12 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 2 mA	1.65 V	0.45			
	I _{OL} = 4 mA	2.3 V	0.4			
	I _{OL} = 6 mA	2.3 V	0.55			
		3 V	0.55			
	I _{OL} = 8 mA	2.7 V	0.6			
	I _{OL} = 12 mA	3 V	0.8			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	V _I = V _{CC} or GND	3.3 V	3.5			pF
C ₀	V _O = V _{CC} or GND	3.3 V	7			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency		§		150		150		150		MHz
t _w	Pulse duration, CLK high or low		§		3.3		3.3		3.3		ns
t _{su}	Setup time	Data before CLK↑	§		4		3.6		3.1		ns
		CLKEN before CLK↑	§		3.4		3.1		2.7		
t _h	Hold time	Data after CLK↑	§		0		0		0		ns
		CLKEN after CLK↑	§		0		0		0		

§ This information was not available at the time of publication.



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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	CLK	Q	†		1	6.7	6.2		1	5.3	ns
t _{en}	OE	Q	†		1	7.2	7		1	5.8	ns
t _{dis}	OE	Q	†		1	6.3	5.4		1	5	ns

† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 50 pF, f = 10 MHz	†	55	59	pF
		Outputs disabled		†	46	49	

† This information was not available at the time of publication.

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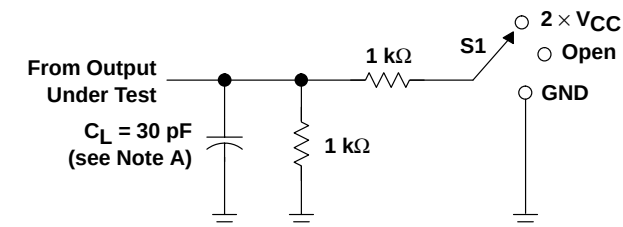
3.3-V 20-BIT FLIP-FLOP

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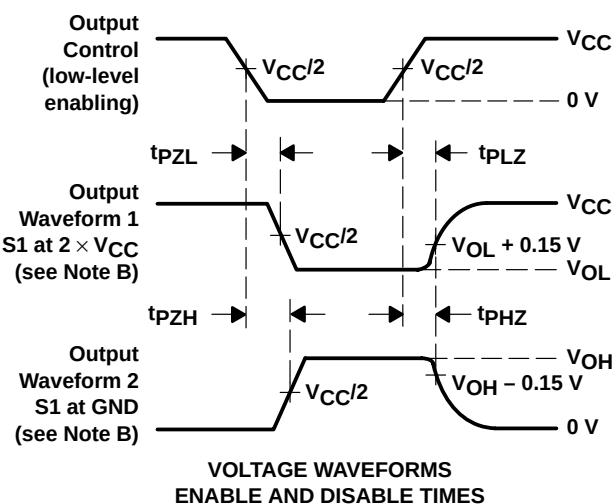
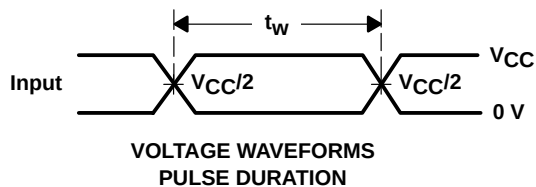
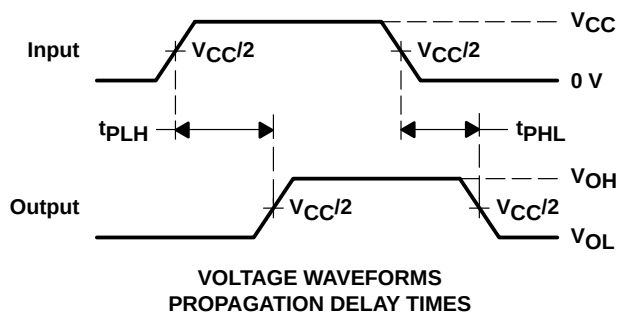
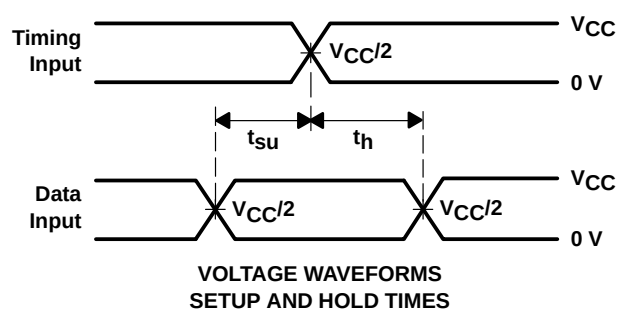
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PHL}	GND

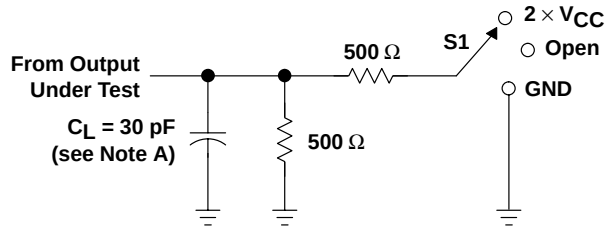


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

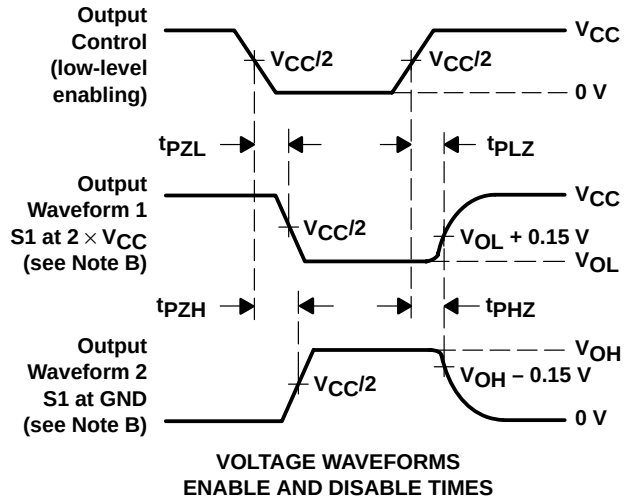
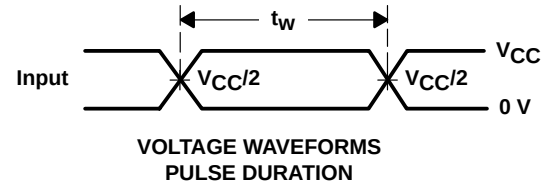
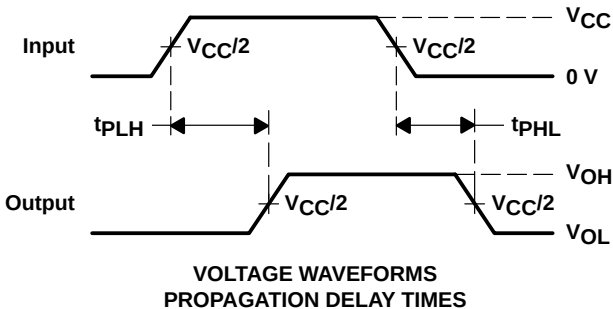
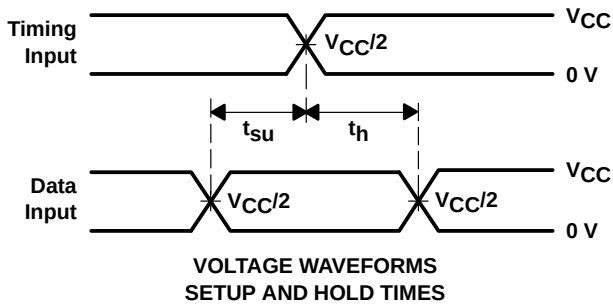
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

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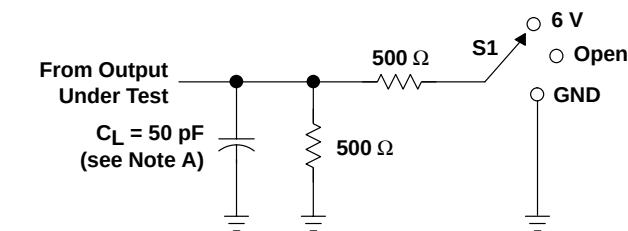
3.3-V 20-BIT FLIP-FLOP

WITH 3-STATE OUTPUTS

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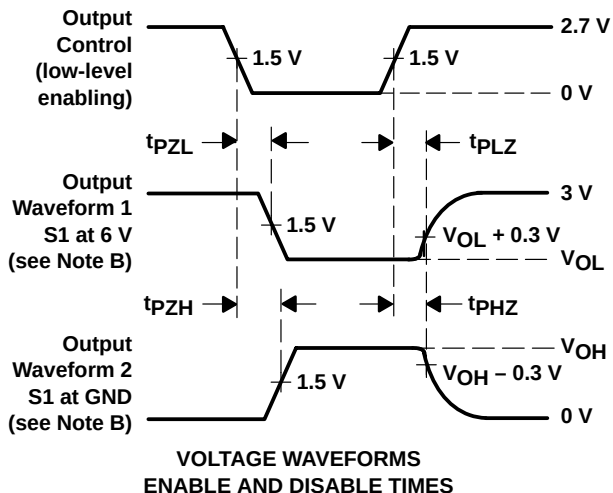
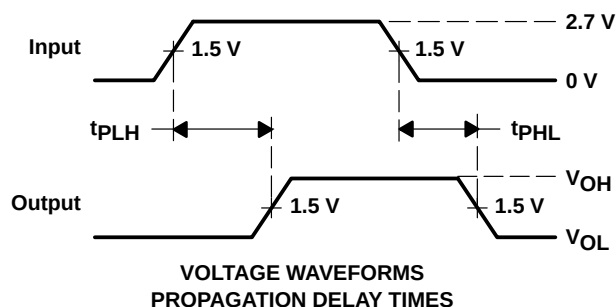
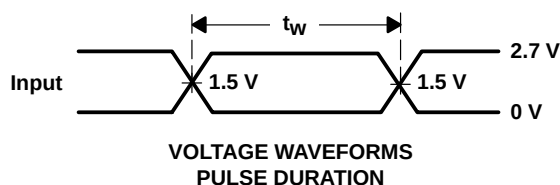
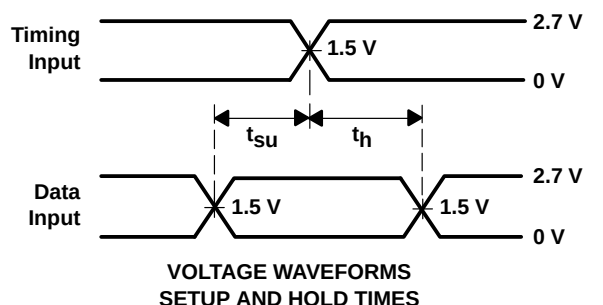
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{pLZ}/t_{pZL}	6 V
t_{pHZ}/t_{pZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

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3.3-V 10-BIT FLIP-FLOP WITH DUAL OUTPUTS AND 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Output Ports Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 10-bit flip-flop is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH162820 flip-flops are edge-triggered D-type flip-flops. On the positive transition of the clock (CLK) input, the device provides true data at the Q outputs.

A buffered output-enable ($\overline{OE}$) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without need for interface or pullup components.

$\overline{OE}$ does not affect the internal operations of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The outputs, which are designed to sink up to 12 mA, include equivalent 26-Ω resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH162820 is characterized for operation from –40°C to 85°C.

DGG OR DL PACKAGE
(TOP VIEW)

1 $\overline{OE}$	1	56	CLK
1Q1	2	55	D1
1Q2	3	54	NC
GND	4	53	GND
2Q1	5	52	D2
2Q2	6	51	NC
V_{CC}	7	50	V_{CC}
3Q1	8	49	D3
3Q2	9	48	NC
4Q1	10	47	D4
GND	11	46	GND
4Q2	12	45	NC
5Q1	13	44	D5
5Q2	14	43	NC
6Q1	15	42	D6
6Q2	16	41	NC
7Q1	17	40	D7
GND	18	39	GND
7Q2	19	38	NC
8Q1	20	37	D8
8Q2	21	36	NC
V_{CC}	22	35	V_{CC}
9Q1	23	34	D9
9Q2	24	33	NC
GND	25	32	GND
10Q1	26	31	D10
10Q2	27	30	NC
2 $\overline{OE}$	28	29	NC

NC – No internal connection

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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AND 3-STATE OUTPUTS

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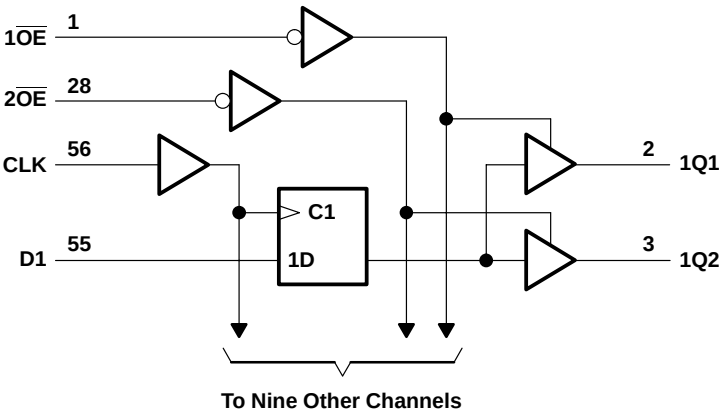
FUNCTION TABLE

(each flip-flop)

INPUTS			OUTPUT Q
$\overline{OE}_n^\dagger$	CLK	D	
L	↑	H	H
L	↑	L	L
L	L	X	Q ₀
H	X	X	Z

$^\dagger n = 1, 2$

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC}	−0.5 V to 4.6 V
Input voltage range, V _I (see Note 1)	−0.5 V to 4.6 V
Output voltage range, V _O (see Notes 1 and 2)	−0.5 V to V _{CC} + 0.5 V
Input clamp current, I _{IK} (V _I < 0)	−50 mA
Output clamp current, I _{OK} (V _O < 0)	−50 mA
Continuous output current, I _O	±50 mA
Continuous current through each V _{CC} or GND	±100 mA
Package thermal impedance, θ _{JA} (see Note 3)	106°C/W
Storage temperature range, T _{stg}	−65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
- The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 - This value is limited to 4.6 V maximum.
 - The package thermal impedance is calculated in accordance with JESD 51.

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recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−2		mA
		V _{CC} = 2.3 V	−6		
		V _{CC} = 2.7 V	−8		
		V _{CC} = 3 V	−12		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	2		mA
		V _{CC} = 2.3 V	6		
		V _{CC} = 2.7 V	8		
		V _{CC} = 3 V	12		
Δt/Δv	Input transition rise or fall rate		10		ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

3.3-V 10-BIT FLIP-FLOP WITH DUAL OUTPUTS AND 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3.5			pF
	Data inputs			6			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency	§		150		150		150		MHz
t _w	Pulse duration, CLK high or low	§		3.3		3.3		3.3		ns
t _{su}	Setup time, data before CLK↑	§		1.7		1.8		1.4		ns
t _h	Hold time, data after CLK↑	§		1.1		1.1		1		ns

§ This information was not available at the time of publication.

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	CLK	Q		†	1	6.4	6.2		1	5.4	ns
t _{en}	$\overline{OE}$	Q		†	1	6.9	6.8		1	5.6	ns
t _{dis}	$\overline{OE}$	Q		†	1	6.2	5.5		1	5	ns

† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance per flip-flop	All outputs enabled	C _L = 50 pF, f = 10 MHz	†	68	66	pF
		All outputs disabled		†	39	47	

† This information was not available at the time of publication.

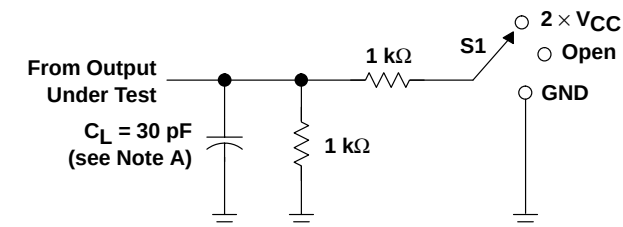
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3.3-V 10-BIT FLIP-FLOP WITH DUAL OUTPUTS AND 3-STATE OUTPUTS

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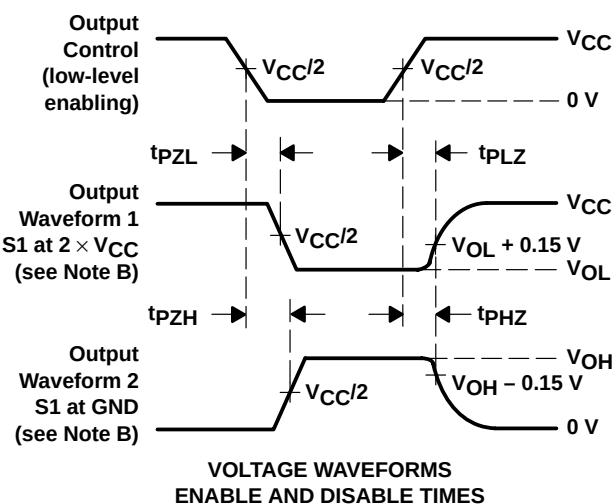
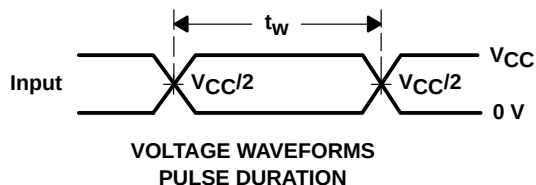
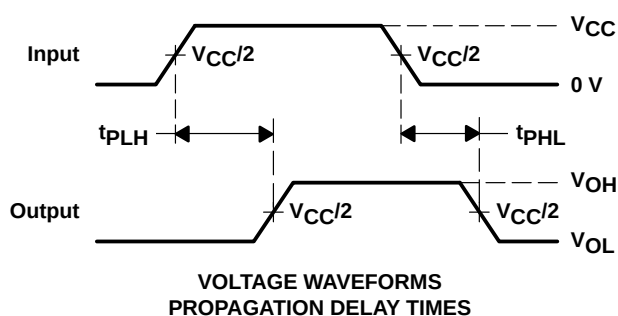
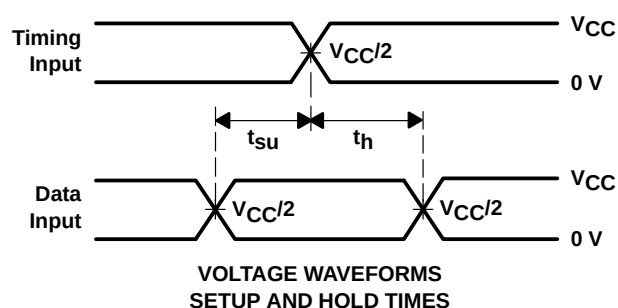
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PHL}	GND

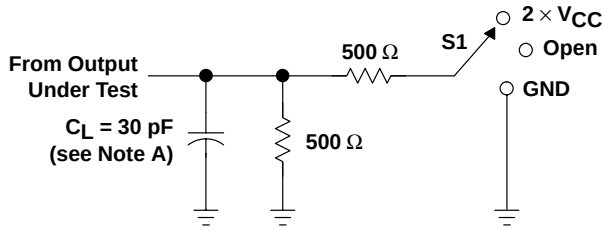


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

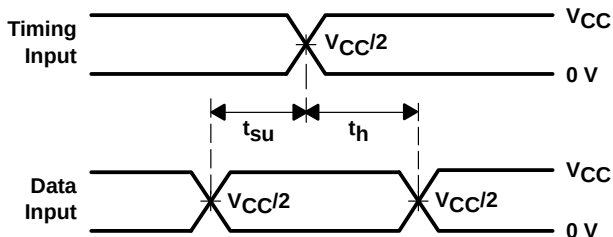
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

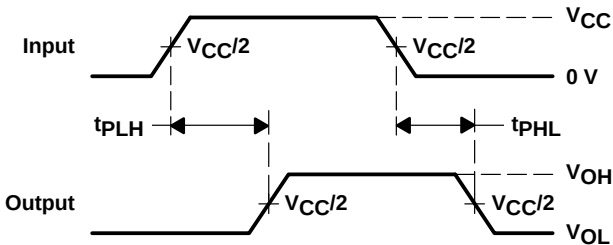


LOAD CIRCUIT

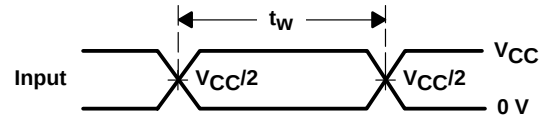
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



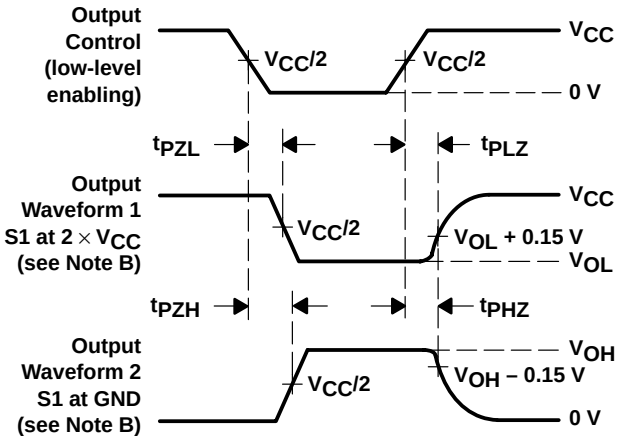
**VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES**



**VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES**



**VOLTAGE WAVEFORMS
PULSE DURATION**



**VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES**

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

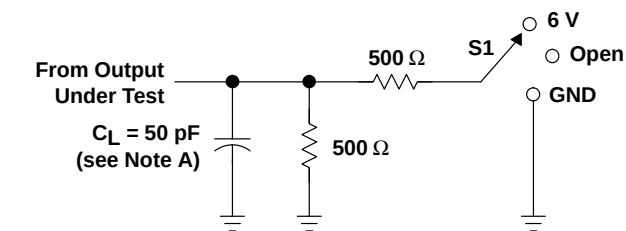
SN74ALVCH162820

3.3-V 10-BIT FLIP-FLOP WITH DUAL OUTPUTS AND 3-STATE OUTPUTS

SCES012E – JULY 1995 – REVISED FEBRUARY 1999

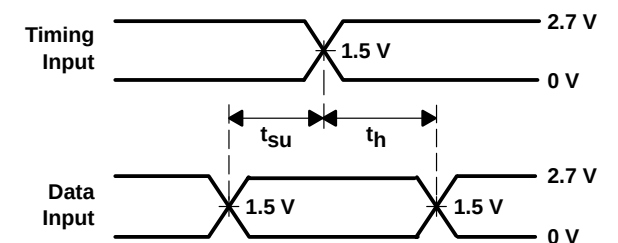
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$

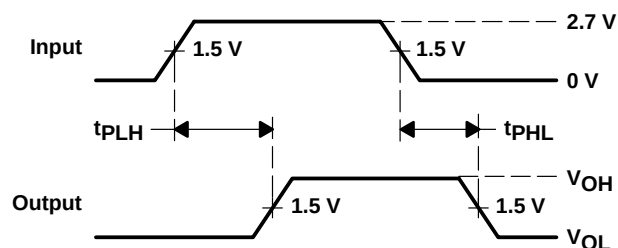


LOAD CIRCUIT

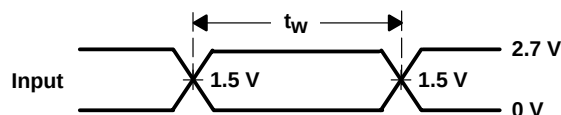
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



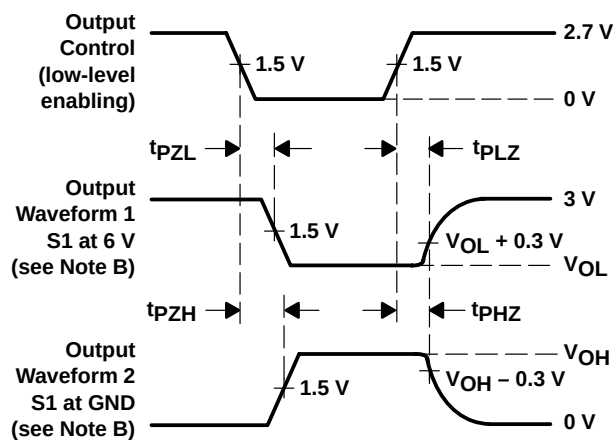
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH162827

20-BIT BUFFER/DRIVER WITH 3-STATE OUTPUTS

SCES013E – JULY 1995 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Output Ports Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages

description

This 20-bit noninverting buffer/driver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH162827 is composed of two 10-bit sections with separate output-enable signals. For either 10-bit buffer section, the two output-enable ($\overline{1OE1}$ and $\overline{1OE2}$ or $\overline{2OE1}$ and $\overline{2OE2}$) inputs must both be low for the corresponding Y outputs to be active. If either output-enable input is high, the outputs of that 10-bit buffer section are in the high-impedance state.

The outputs, which are designed to sink up to 12 mA, include equivalent 26-Ω resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH162827 is characterized for operation from –40°C to 85°C.

DGG, DGV, OR DL PACKAGE (TOP VIEW)

$\overline{1OE1}$	1	56	$\overline{1OE2}$
1Y1	2	55	1A1
1Y2	3	54	1A2
GND	4	53	GND
1Y3	5	52	1A3
1Y4	6	51	1A4
V_{CC}	7	50	V_{CC}
1Y5	8	49	1A5
1Y6	9	48	1A6
1Y7	10	47	1A7
GND	11	46	GND
1Y8	12	45	1A8
1Y9	13	44	1A9
1Y10	14	43	1A10
2Y1	15	42	2A1
2Y2	16	41	2A2
2Y3	17	40	2A3
GND	18	39	GND
2Y4	19	38	2A4
2Y5	20	37	2A5
2Y6	21	36	2A6
V_{CC}	22	35	V_{CC}
2Y7	23	34	2A7
2Y8	24	33	2A8
GND	25	32	GND
2Y9	26	31	2A9
2Y10	27	30	2A10
$\overline{2OE1}$	28	29	$\overline{2OE2}$

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



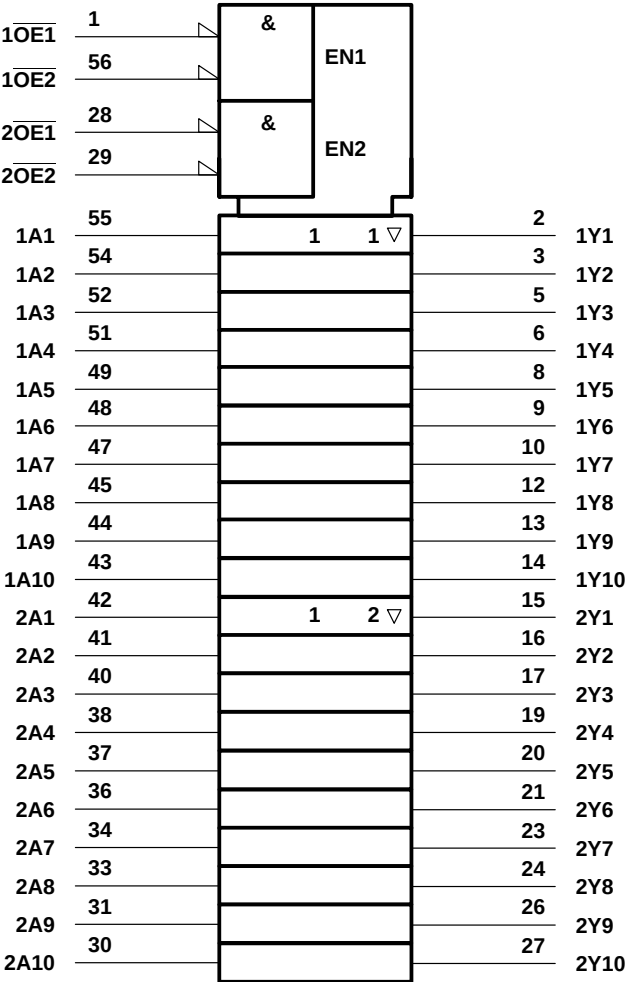
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FUNCTION TABLE
(each 10-bit section)

INPUTS			OUTPUT Y
OE1	OE2	A	
L	L	L	L
L	L	H	H
H	X	X	Z
X	H	X	Z

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Supply voltage range, V_{CC}		-0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)		-0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)		-0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)		-50 mA
Output clamp current, I_{OK} ($V_O < 0$)		-50 mA
Continuous output current, I_O		± 50 mA
Continuous current through each V_{CC} or GND		± 100 mA
Package thermal impedance, θ_{JA} (see Note 3):		
DGG package		81°C/W
DGV package		86°C/W
DL package		74°C/W
Storage temperature range, T_{stg}		-65°C to 150°C

NOTES:

1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JEDEC 51.

SN74ALVCH162827
20-BIT BUFFER/DRIVER
WITH 3-STATE OUTPUTS

SCES013E – JULY 1995 – REVISED FEBRUARY 1999

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–2	mA
		$V_{CC} = 2.3 \text{ V}$	–6	
		$V_{CC} = 2.7 \text{ V}$	–8	
		$V_{CC} = 3 \text{ V}$	–12	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	2	mA
		$V_{CC} = 2.3 \text{ V}$	6	
		$V_{CC} = 2.7 \text{ V}$	8	
		$V_{CC} = 3 \text{ V}$	12	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V			±5	µA
I _I (hold)		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V			±500	
I _{OZ}		V _O = V _{CC} or GND	3.6 V			±10	µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V			40	µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V			750	µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3.5			pF
	Data inputs			6			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

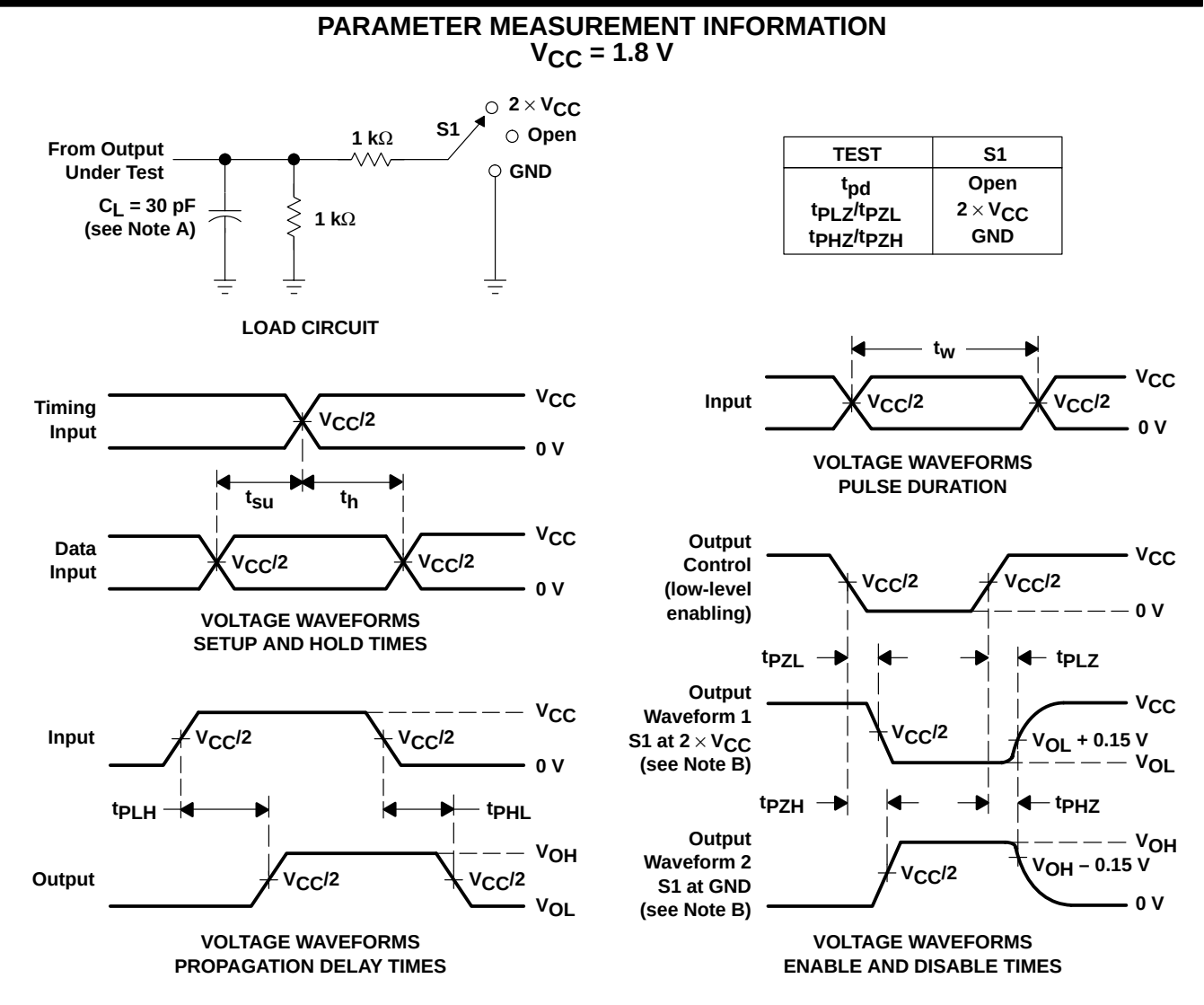
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	Y	§	1	4.4	4.4		1.5	3.8	ns
t _{en}	$\overline{\text{OE}}$	Y	§	1.4	6.3	6.2		1.6	5.1	ns
t _{dis}	$\overline{\text{OE}}$	Y	§	1.7	5.9	5.2		1.8	4.7	ns

§ This information was not available at the time of publication.

operating characteristics, $T_A = 25^{\circ}\text{C}$

PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd} Power dissipation capacitance	Outputs enabled	$C_L = 50\text{ pF}, f = 10\text{ MHz}$	†	16	18	pF
	Outputs disabled		†	4	6	

† This information was not available at the time of publication.



- NOTES:
- A. C_L includes probe and jig capacitance.

B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.

D. The outputs are measured one at a time with one transition per measurement.

E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .

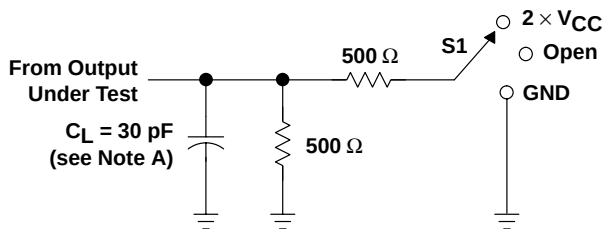
F. t_{PZL} and t_{PZH} are the same as t_{en} .

G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

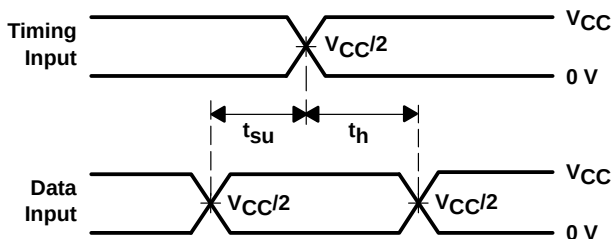
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

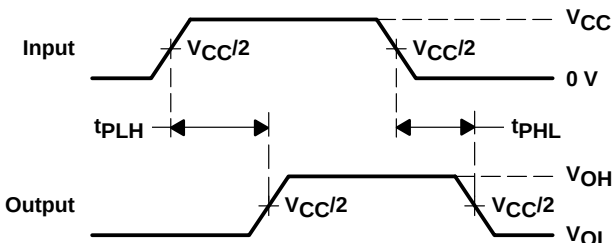


LOAD CIRCUIT

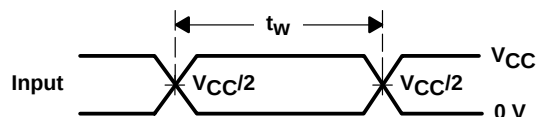
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



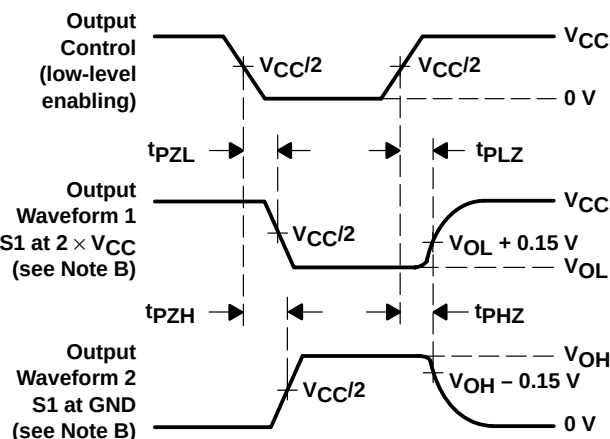
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES: A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
- D. The outputs are measured one at a time with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH162827

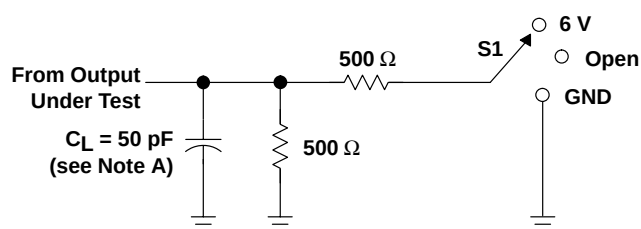
20-BIT BUFFER/DRIVER

WITH 3-STATE OUTPUTS

SCES013E – JULY 1995 – REVISED FEBRUARY 1999

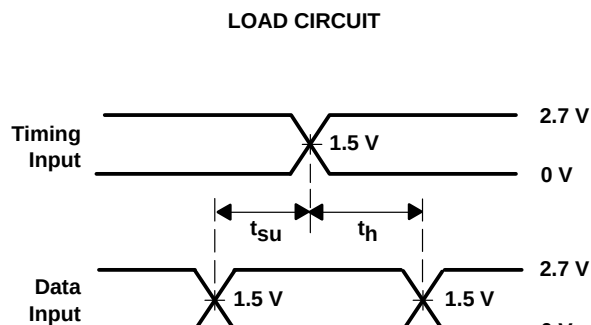
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

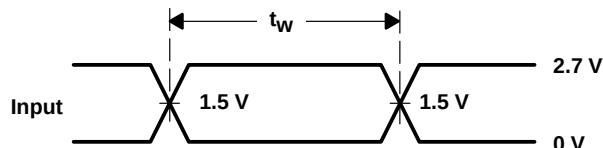


LOAD CIRCUIT

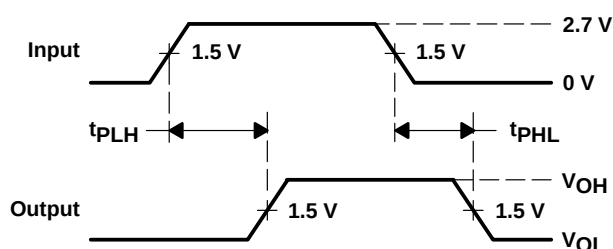
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



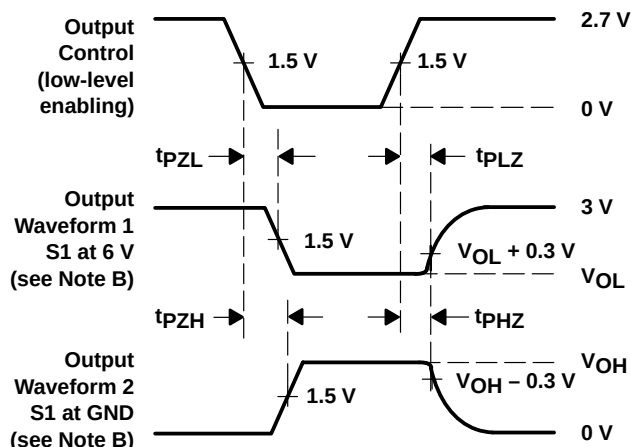
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH162830

1-BIT TO 2-BIT ADDRESS DRIVER WITH 3-STATE OUTPUTS

SCES082F – AUGUST 1996 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Output Ports Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Packaged in Thin Very Small-Outline Package

description

This 1-bit to 2-bit address driver is designed for 1.65-V to 3.6-V V_{CC} operation.

Active bus-hold circuitry is provided to hold unused or floating inputs at a valid logic level.

The outputs, which are designed to sink up to 12 mA, include equivalent 26-Ω resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74ALVCH162830 is characterized for operation from –40°C to 85°C.

DBB PACKAGE
(TOP VIEW)

2Y2	1	80	1Y3
1Y2	2	79	2Y3
GND	3	78	GND
2Y1	4	77	1Y4
1Y1	5	76	2Y4
V_{CC}	6	75	V_{CC}
A1	7	74	1Y5
A2	8	73	2Y5
GND	9	72	GND
A3	10	71	1Y6
A4	11	70	2Y6
GND	12	69	GND
A5	13	68	1Y7
A6	14	67	2Y7
V_{CC}	15	66	V_{CC}
A7	16	65	1Y8
A8	17	64	2Y8
GND	18	63	GND
A9	19	62	1Y9
$\overline{OE1}$	20	61	2Y9
$\overline{OE2}$	21	60	1Y10
A10	22	59	2Y10
GND	23	58	GND
A11	24	57	1Y11
A12	25	56	2Y11
V_{CC}	26	55	V_{CC}
A13	27	54	1Y12
A14	28	53	2Y12
GND	29	52	GND
A15	30	51	1Y13
A16	31	50	2Y13
GND	32	49	GND
A17	33	48	1Y14
A18	34	47	2Y14
V_{CC}	35	46	V_{CC}
2Y18	36	45	1Y15
1Y18	37	44	2Y15
GND	38	43	GND
2Y17	39	42	1Y16
1Y17	40	41	2Y16

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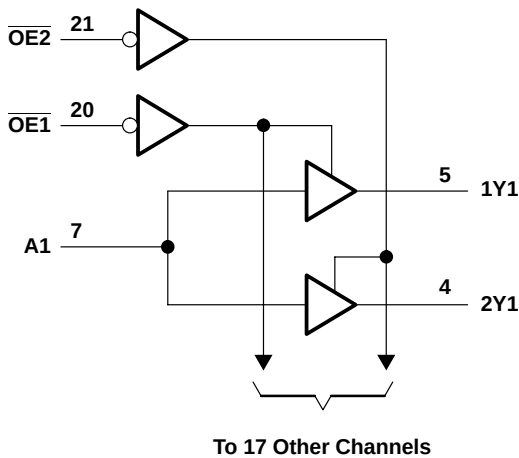
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FUNCTION TABLE

INPUTS			OUTPUTS	
OE1	OE2	A	1Yn	2Yn
L	H	H	H	Z
L	H	L	L	Z
H	L	H	Z	H
H	L	L	Z	L
L	L	H	H	H
L	L	L	L	L
H	H	X	Z	Z

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3)	106°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

SN74ALVCH162830
1-BIT TO 2-BIT ADDRESS DRIVER
WITH 3-STATE OUTPUTS

SCES082F – AUGUST 1996 – REVISED FEBRUARY 1999

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−2		mA
		V _{CC} = 2.3 V	−6		
		V _{CC} = 2.7 V	−8		
		V _{CC} = 3 V	−12		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	2		mA
		V _{CC} = 2.3 V	6		
		V _{CC} = 2.7 V	8		
		V _{CC} = 3 V	12		
Δt/Δv	Input transition rise or fall rate			10	ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

**1-BIT TO 2-BIT ADDRESS DRIVER
WITH 3-STATE OUTPUTS**

SCES082F – AUGUST 1996 – REVISED FEBRUARY 1999

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}	I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
	I _{OH} = –2 mA	1.65 V	1.2			
	I _{OH} = –4 mA	2.3 V	1.9			
	I _{OH} = –6 mA	2.3 V	1.7			
		3 V	2.4			
	I _{OH} = –8 mA	2.7 V	2			
	I _{OH} = –12 mA	3 V	2			
V _{OL}	I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
	I _{OL} = 2 mA	1.65 V	0.45			
	I _{OL} = 4 mA	2.3 V	0.4			
	I _{OL} = 6 mA	2.3 V	0.55			
		3 V	0.55			
	I _{OL} = 8 mA	2.7 V	0.6			
	I _{OL} = 12 mA	3 V	0.8			
I _I	V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)	V _I = 0.58 V	1.65 V	25			µA
	V _I = 1.07 V	1.65 V	–25			
	V _I = 0.7 V	2.3 V	45			
	V _I = 1.7 V	2.3 V	–45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V	3 V	–75			
	V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}	V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	4.5			pF
	Data inputs		5			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7.5		pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	Y	§	1.2	3.8	4		1.7	3.5	ns
t _{en}	$\overline{\text{OE}}$	Y	§	1	5.7	5.7		1	4.8	ns
t _{dis}	$\overline{\text{OE}}$	Y	§	1.5	6.2	5.4		1.7	5.2	ns

[§] This information was not available at the time of publication.

SN74ALVCH162830

1-BIT TO 2-BIT ADDRESS DRIVER WITH 3-STATE OUTPUTS

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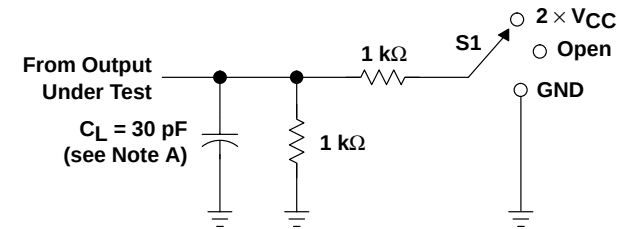
operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd} Power dissipation capacitance	All outputs enabled	$C_L = 0$, $f = 10\text{ MHz}$	†	50	54	pF
	All outputs disabled		†	8	8	

† This information was not available at the time of publication.

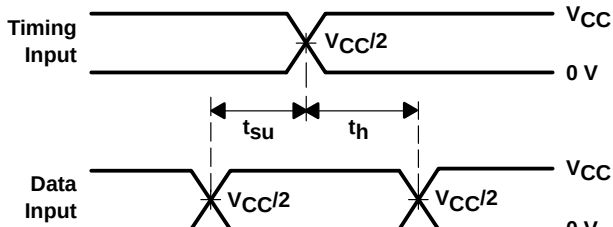
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8\text{ V}$

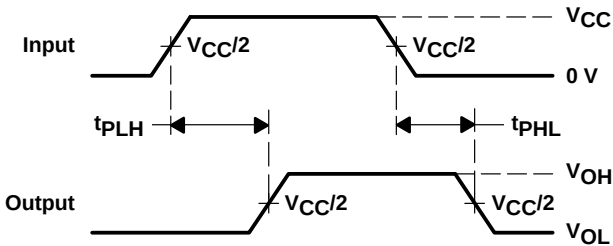


LOAD CIRCUIT

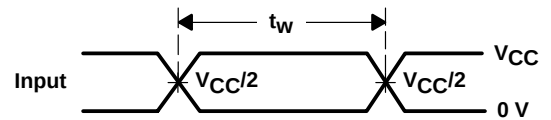
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



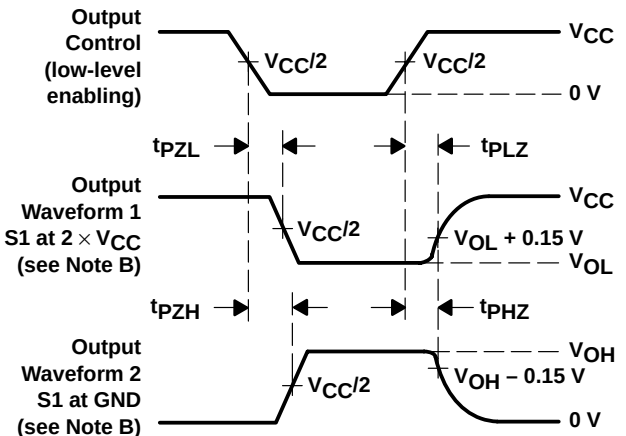
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms



SN74ALVCH162830

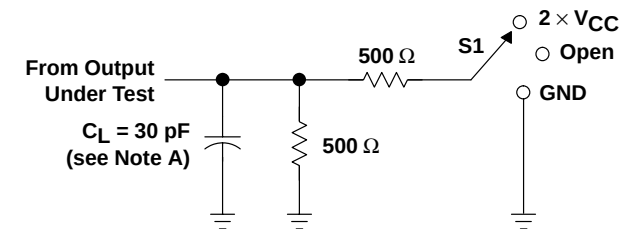
1-BIT TO 2-BIT ADDRESS DRIVER

WITH 3-STATE OUTPUTS

SCES082F – AUGUST 1996 – REVISED FEBRUARY 1999

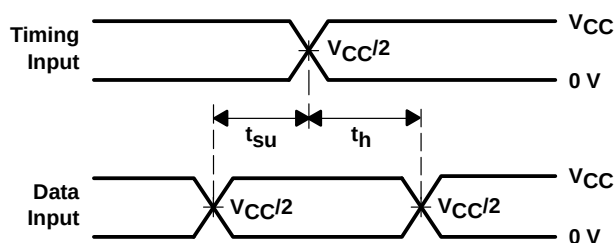
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

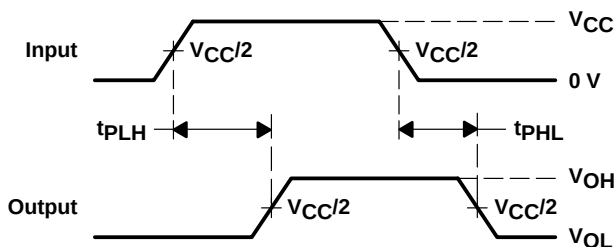


LOAD CIRCUIT

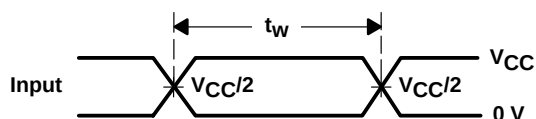
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



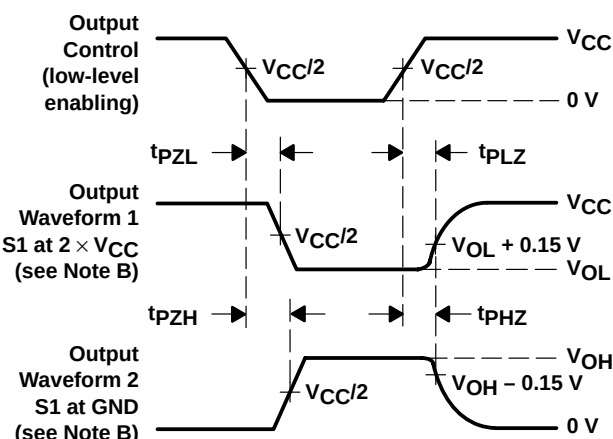
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



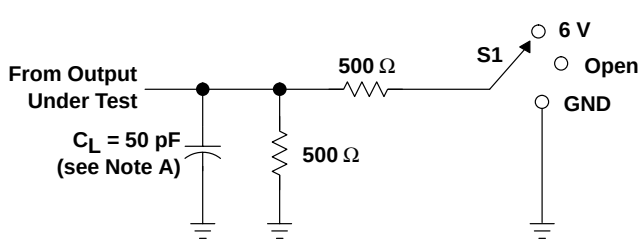
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

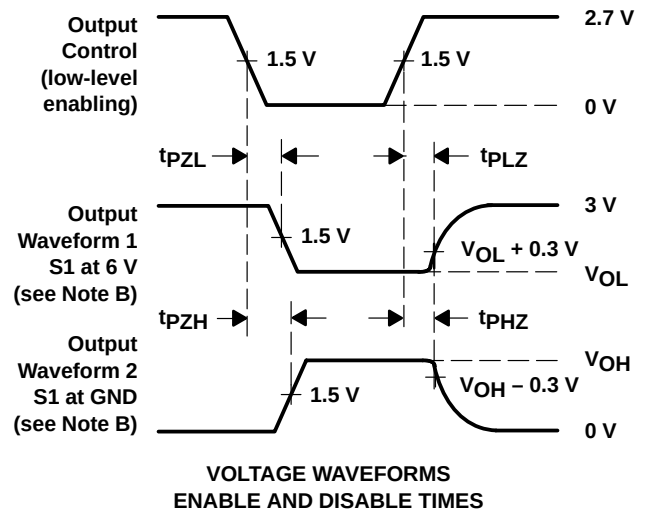
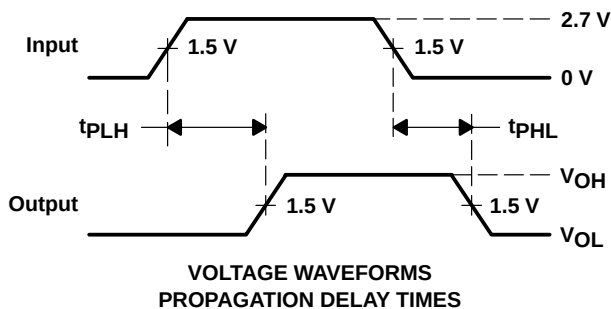
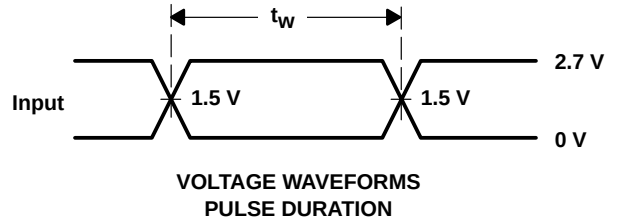
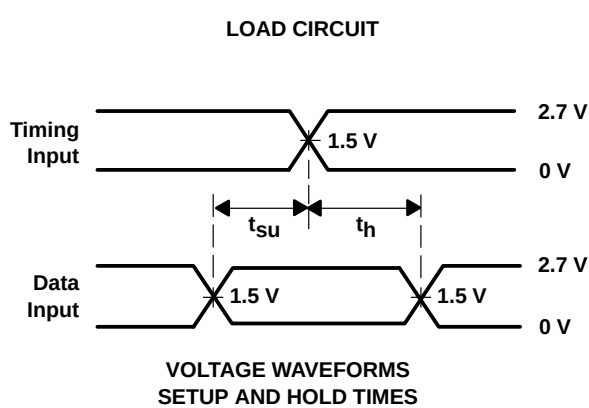
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES: A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
- D. The outputs are measured one at a time with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVC162831

1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER WITH 3-STATE OUTPUTS

SCAS605A – APRIL 1998 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Output Ports Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Packaged in Thin Very Small-Outline Package

description

This 1-bit to 4-bit address register/driver is designed for 1.65-V to 3.6-V V_{CC} operation.

The device is ideal for use in applications in which a single address bus is driving four separate memory locations. The SN74ALVC162831 can be used as a buffer or a register, depending on the logic level of the select ($\overline{SEL}$) input.

When $\overline{SEL}$ is logic high, the device is in the buffer mode. The outputs follow the inputs and are controlled by the two output-enable ($\overline{OE}$) inputs. Each $\overline{OE}$ controls two groups of nine outputs.

When $\overline{SEL}$ is logic low, the device is in the register mode. The register is an edge-triggered D-type flip-flop. On the positive transition of the clock (CLK) input, data set up at the A inputs is stored in the internal registers. $\overline{OE}$ controls operate the same as in buffer mode.

When $\overline{OE}$ is logic low, the outputs are in a normal logic state (high or low logic level). When $\overline{OE}$ is logic high, the outputs are in the high-impedance state.

$\overline{SEL}$ and $\overline{OE}$ do not affect the internal operation of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

DBB PACKAGE (TOP VIEW)

4Y1	1	80	1Y2
3Y1	2	79	2Y2
GND	3	78	GND
2Y1	4	77	3Y2
1Y1	5	76	4Y2
V_{CC}	6	75	V_{CC}
NC	7	74	1Y3
A1	8	73	2Y3
GND	9	72	GND
NC	10	71	3Y3
A2	11	70	4Y3
GND	12	69	GND
NC	13	68	1Y4
A3	14	67	2Y4
V_{CC}	15	66	V_{CC}
NC	16	65	3Y4
A4	17	64	4Y4
GND	18	63	GND
CLK	19	62	1Y5
$\overline{OE1}$	20	61	2Y5
$\overline{OE2}$	21	60	3Y5
$\overline{SEL}$	22	59	4Y5
GND	23	58	GND
A5	24	57	1Y6
A6	25	56	2Y6
V_{CC}	26	55	V_{CC}
A7	27	54	3Y6
NC	28	53	4Y6
GND	29	52	GND
A8	30	51	1Y7
NC	31	50	2Y7
GND	32	49	GND
A9	33	48	3Y7
NC	34	47	4Y7
V_{CC}	35	46	V_{CC}
4Y9	36	45	1Y8
3Y9	37	44	2Y8
GND	38	43	GND
2Y9	39	42	3Y8
1Y9	40	41	4Y8

NC – No internal connection

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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SN74ALVC162831
1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER
WITH 3-STATE OUTPUTS

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description (continued)

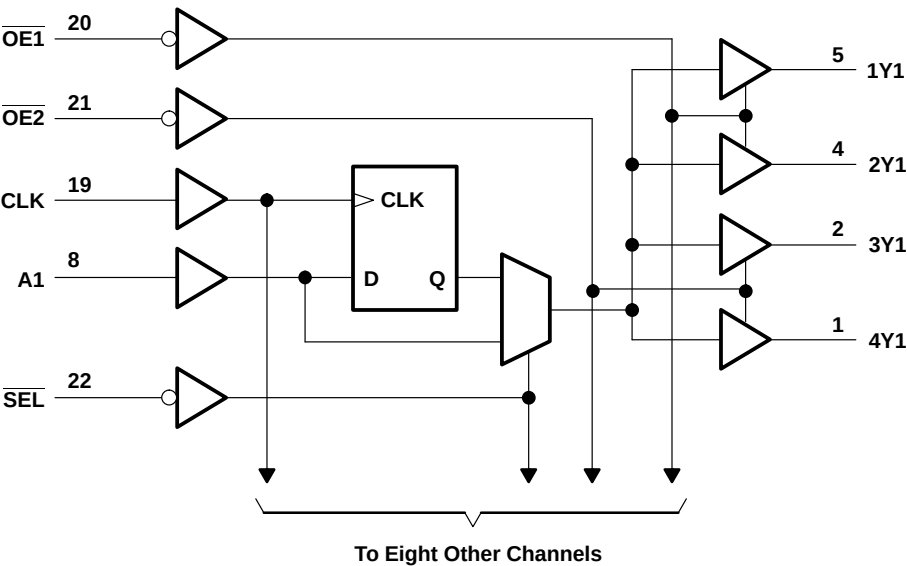
The outputs, which are designed to sink up to 12 mA, include equivalent 26-Ω resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74ALVC162831 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE				
INPUTS				OUTPUT Y
$\overline{OE}$	$\overline{SEL}$	CLK	A	
H	X	X	X	Z
L	H	X	L	L
L	H	X	H	H
L	L	↑	L	L
L	L	↑	H	H

logic diagram (positive logic)



SN74ALVC162831
1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER
WITH 3-STATE OUTPUTS

SCAS605A – APRIL 1998 – REVISED FEBRUARY 1999

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3)	106°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		1.65	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	1.7		
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.35 × V _{CC}		V
		V _{CC} = 2.3 V to 2.7 V	0.7		
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 1.65 V	−2		mA
		V _{CC} = 2.3 V	−6		
		V _{CC} = 2.7 V	−8		
		V _{CC} = 3 V	−12		
I _{OL}	Low-level output current	V _{CC} = 1.65 V	2		mA
		V _{CC} = 2.3 V	6		
		V _{CC} = 2.7 V	8		
		V _{CC} = 3 V	12		
Δt/Δv	Input transition rise or fall rate		10		ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER WITH 3-STATE OUTPUTS

SCAS605A – APRIL 1998 – REVISED FEBRUARY 1999

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	4.5			pF
	Data inputs			4.5			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency		‡	150		150		150		MHz
t _w	Pulse duration, CLK high or low		‡	3.3		3.3		3.3		ns
t _{su}	Setup time, A data before CLK↑		‡	2		2		1.6		ns
t _h	Hold time, A data after CLK↑		‡	0.7		0.5		1.1		ns

‡ This information was not available at the time of publication.

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1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER
WITH 3-STATE OUTPUTS

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	A	Y		†	1.1	4.7	4.8		1.5	4.3	ns
	CLK			†	1	5.3	5.3		1.4	4.7	
	$\overline{\text{SEL}}$			†	1.1	6	6.2		1.5	4.8	
t _{en}	$\overline{\text{OE}}$	Y		†	1	5.9	5.9		1.1	5.1	ns
t _{dis}	$\overline{\text{OE}}$	Y		†	1	5.4	5.4		1.6	5.1	ns

† This information was not available at the time of publication.

switching characteristics from 0°C to 65°C, C_L = 50 pF

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 3.3 V ± 0.15 V		UNIT
			MIN	MAX	
t _{pd}	CLK	Y	1.9	4.5	ns

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 0, f = 10 MHz	†	119	132	pF
		Outputs disabled		†	22	25	

† This information was not available at the time of publication.



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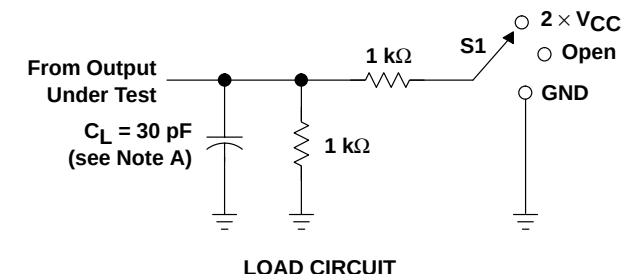
1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER

WITH 3-STATE OUTPUTS

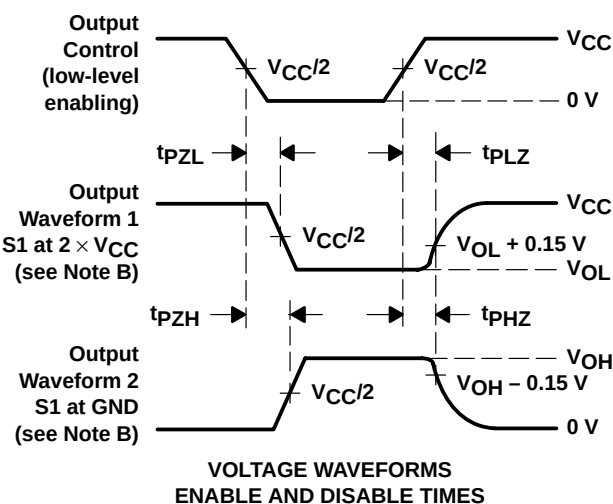
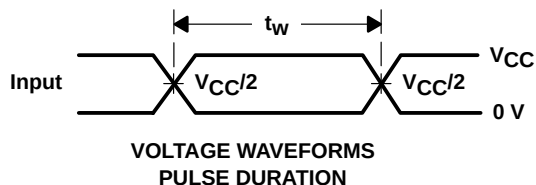
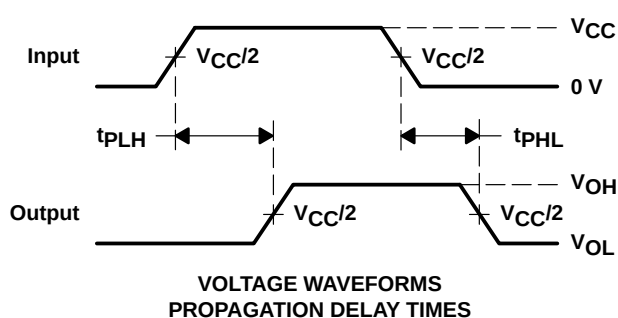
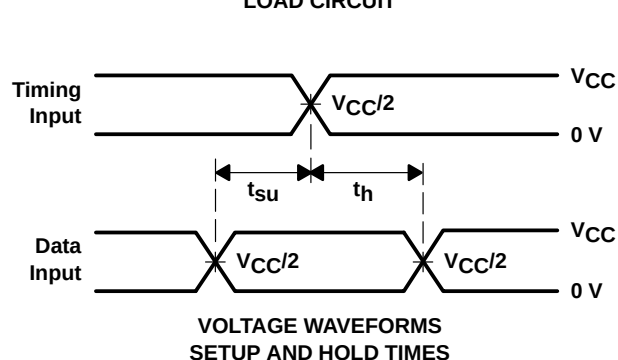
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PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8\text{ V}$



TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PHZ}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

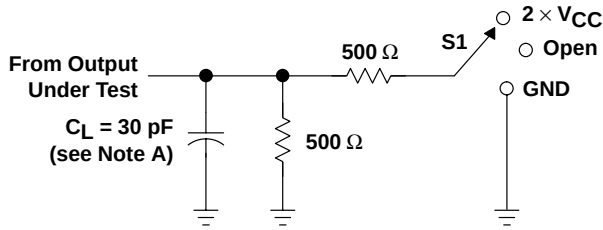
Figure 1. Load Circuit and Voltage Waveforms

SN74ALVC162831
1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER
WITH 3-STATE OUTPUTS

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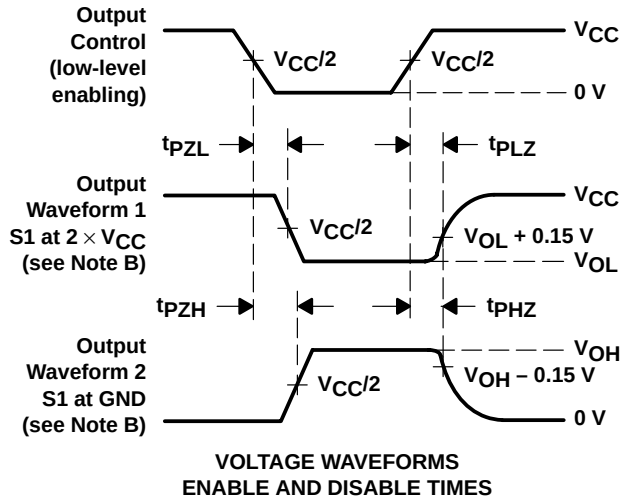
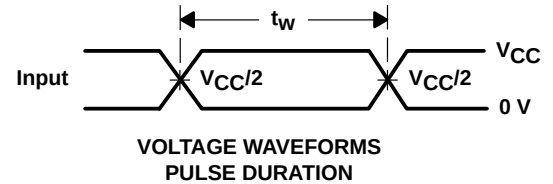
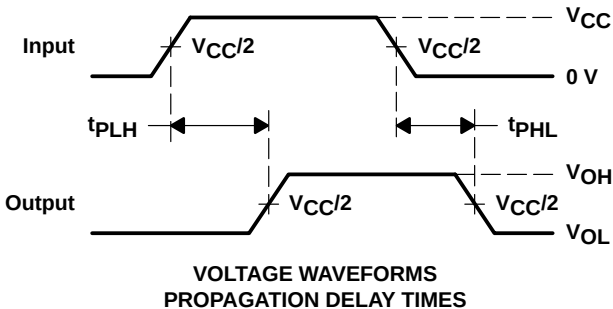
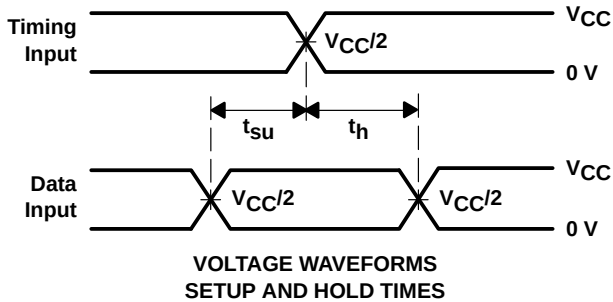
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES: A. C_L includes probe and jig capacitance.
 B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 D. The outputs are measured one at a time with one transition per measurement.
 E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 F. t_{PZL} and t_{PZH} are the same as t_{en} .
 G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

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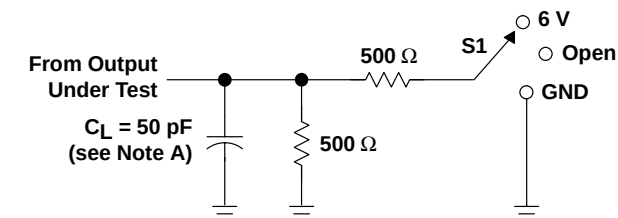
1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER

WITH 3-STATE OUTPUTS

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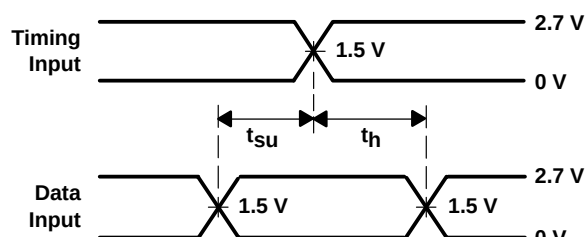
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

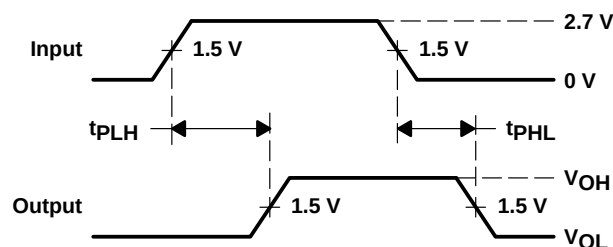


LOAD CIRCUIT

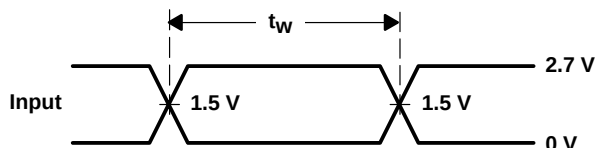
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



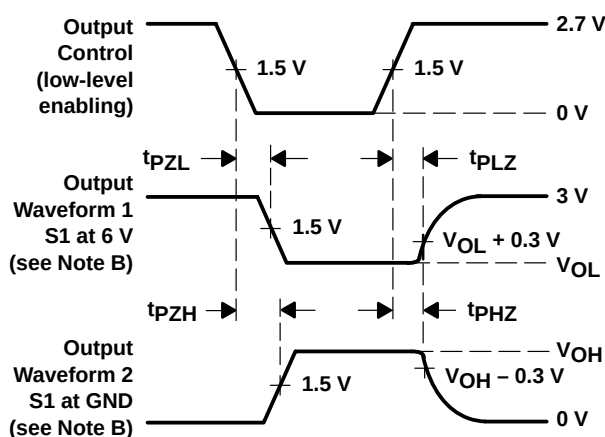
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

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1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER

WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Output Ports Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Packaged in Thin Very Small-Outline Package

description

This 1-bit to 4-bit address register/driver is designed for 1.65-V to 3.6-V V_{CC} operation.

The device is ideal for use in applications in which a single address bus is driving four separate memory locations. The SN74ALVCH162831 can be used as a buffer or a register, depending on the logic level of the select (SEL) input.

When $\overline{SEL}$ is logic high, the device is in the buffer mode. The outputs follow the inputs and are controlled by the two output-enable ($\overline{OE}$) inputs. Each $\overline{OE}$ controls two groups of nine outputs.

When $\overline{SEL}$ is logic low, the device is in the register mode. The register is an edge-triggered D-type flip-flop. On the positive transition of the clock (CLK) input, data set up at the A inputs is stored in the internal registers. $\overline{OE}$ controls operate the same as in buffer mode.

When $\overline{OE}$ is logic low, the outputs are in a normal logic state (high or low logic level). When $\overline{OE}$ is logic high, the outputs are in the high-impedance state.

$\overline{SEL}$ and $\overline{OE}$ do not affect the internal operation of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

DBB PACKAGE (TOP VIEW)

4Y1	1	80	1Y2
3Y1	2	79	2Y2
GND	3	78	GND
2Y1	4	77	3Y2
1Y1	5	76	4Y2
V_{CC}	6	75	V_{CC}
NC	7	74	1Y3
A1	8	73	2Y3
GND	9	72	GND
NC	10	71	3Y3
A2	11	70	4Y3
GND	12	69	GND
NC	13	68	1Y4
A3	14	67	2Y4
V_{CC}	15	66	V_{CC}
NC	16	65	3Y4
A4	17	64	4Y4
GND	18	63	GND
CLK	19	62	1Y5
$\overline{OE1}$	20	61	2Y5
$\overline{OE2}$	21	60	3Y5
$\overline{SEL}$	22	59	4Y5
GND	23	58	GND
A5	24	57	1Y6
A6	25	56	2Y6
V_{CC}	26	55	V_{CC}
A7	27	54	3Y6
NC	28	53	4Y6
GND	29	52	GND
A8	30	51	1Y7
NC	31	50	2Y7
GND	32	49	GND
A9	33	48	3Y7
NC	34	47	4Y7
V_{CC}	35	46	V_{CC}
4Y9	36	45	1Y8
3Y9	37	44	2Y8
GND	38	43	GND
2Y9	39	42	3Y8
1Y9	40	41	4Y8

NC – No internal connection

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1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER
WITH 3-STATE OUTPUTS

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description (continued)

The outputs, which are designed to sink up to 12 mA, include equivalent 26-Ω resistors to reduce overshoot and undershoot.

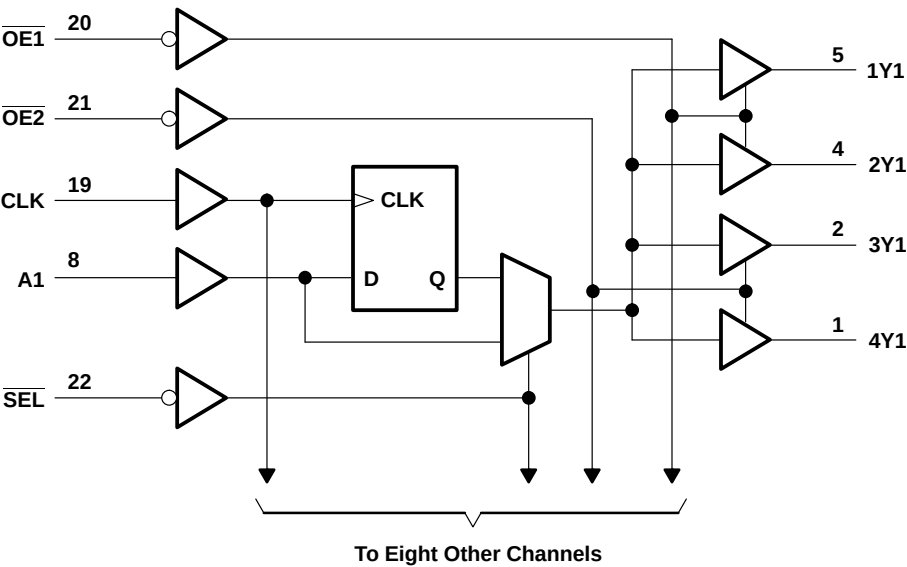
To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH162831 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE				
INPUTS				OUTPUT Y
$\overline{OE}$	$\overline{SEL}$	CLK	A	
H	X	X	X	Z
L	H	X	L	L
L	H	X	H	H
L	L	↑	L	L
L	L	↑	H	H

logic diagram (positive logic)



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1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER WITH 3-STATE OUTPUTS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3)	106°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–2	mA
		$V_{CC} = 2.3$ V	–6	
		$V_{CC} = 2.7$ V	–8	
		$V_{CC} = 3$ V	–12	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	2	mA
		$V_{CC} = 2.3$ V	6	
		$V_{CC} = 2.7$ V	8	
		$V_{CC} = 3$ V	12	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



**1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER
WITH 3-STATE OUTPUTS**

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} – 0.2			V
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{I(hold)}		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	4.5			pF
	Data inputs			5			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency	§		150		150		150		MHz
t _w	Pulse duration, CLK high or low	§		3.3		3.3		3.3		ns
t _{su}	Setup time, A data before CLK↑	§		2		2		1.6		ns
t _h	Hold time, A data after CLK↑	§		0.7		0.5		1.1		ns

[§] This information was not available at the time of publication.

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	A	Y		†	1.1	4.7	4.8		1.5	4.3	ns
	CLK			†	1	5.3	5.3		1.4	4.7	
	$\overline{\text{SEL}}$			†	1.1	6	6.2		1.5	4.8	
t _{en}	$\overline{\text{OE}}$	Y		†	1	5.9	5.9		1.1	5.1	ns
t _{dis}	$\overline{\text{OE}}$	Y		†	1.4	6.3	5.4		1.6	5.1	ns

† This information was not available at the time of publication.

switching characteristics from 0°C to 65°C, C_L = 50 pF

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 3.3 V ± 0.15 V		UNIT
			MIN	MAX	
t _{pd}	CLK	Y	1.9	4.5	ns

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd} Power dissipation capacitance	All outputs enabled	C _L = 0, f = 10 MHz		†	119	132	pF
	All outputs disabled			†	22	25	

† This information was not available at the time of publication.



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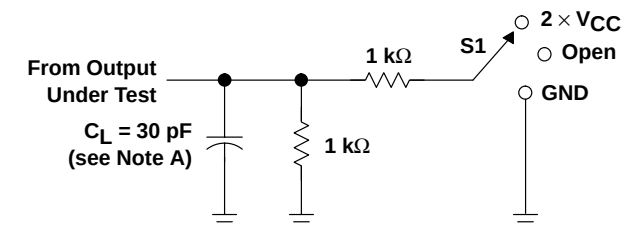
1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER

WITH 3-STATE OUTPUTS

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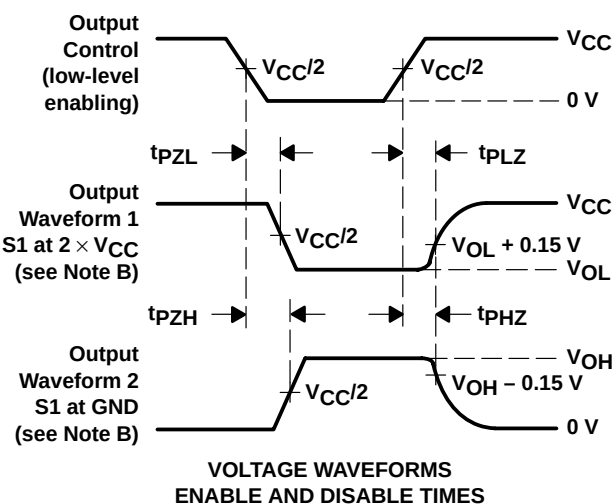
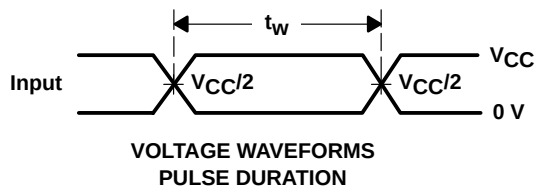
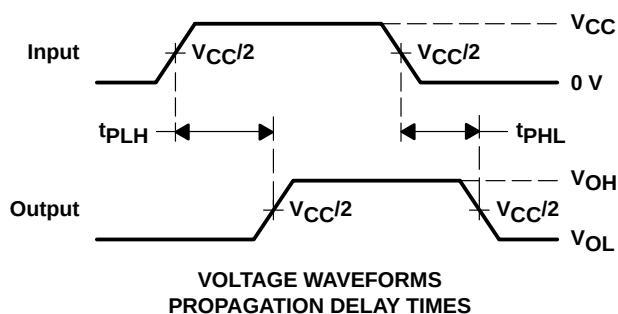
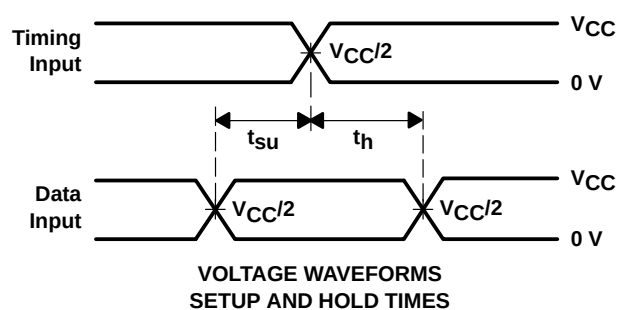
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times$ V_{CC}
t_{PHZ}/t_{PHL}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH162831

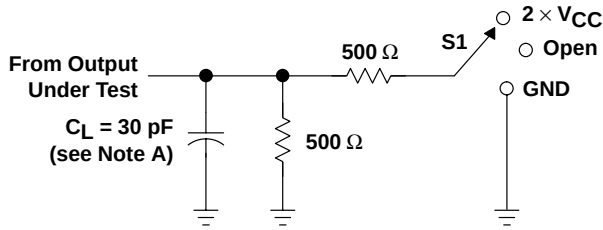
1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER

WITH 3-STATE OUTPUTS

SCES084E – AUGUST 1996 – REVISED FEBRUARY 1999

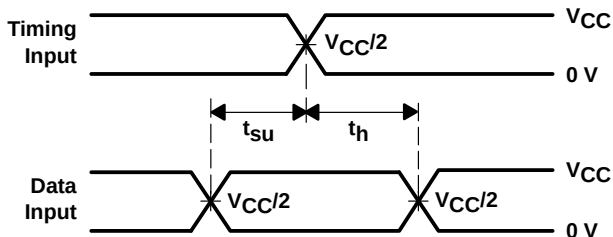
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

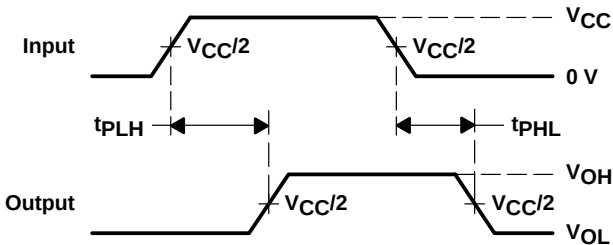


LOAD CIRCUIT

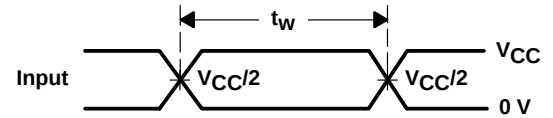
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	$2 \times V_{CC}$
t_{PHZ}/t_{PZH}	GND



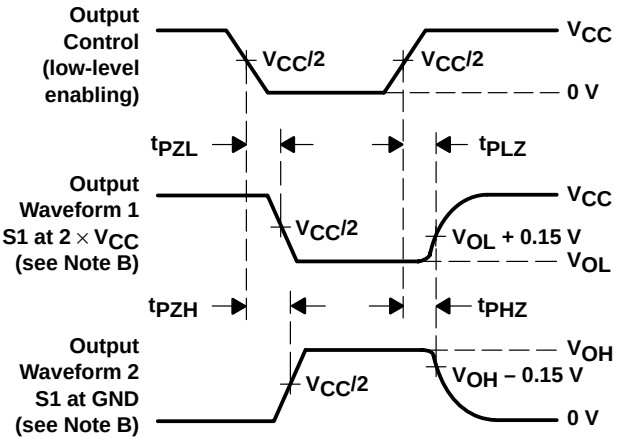
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH162831

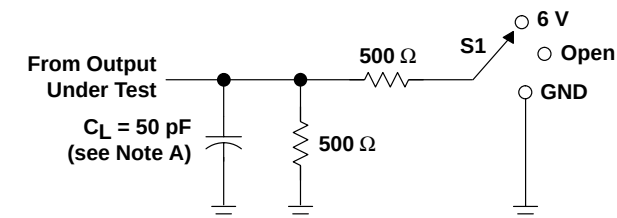
1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER

WITH 3-STATE OUTPUTS

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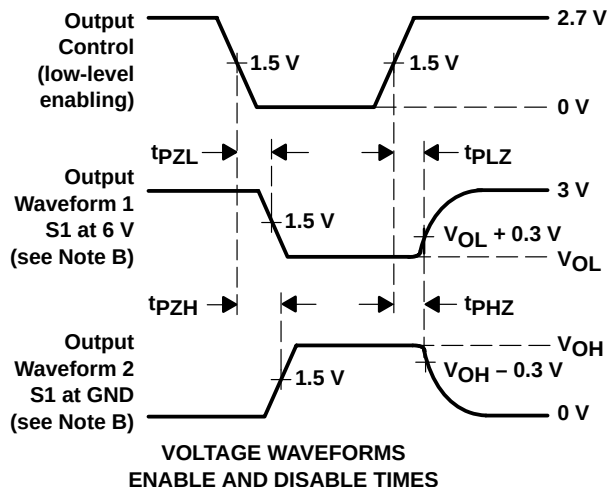
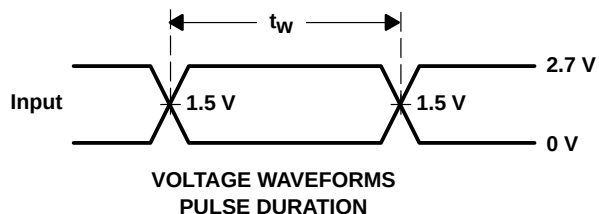
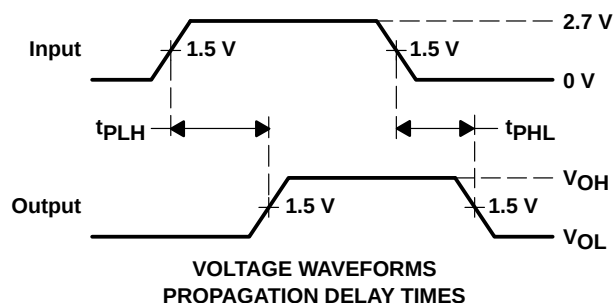
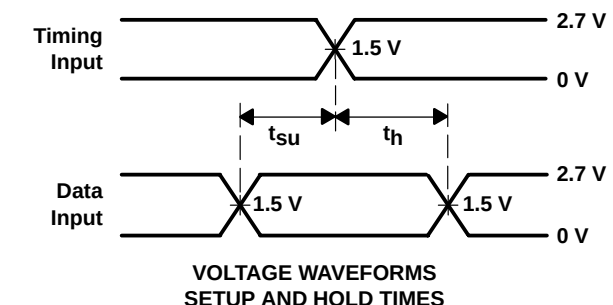
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH162832

1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER

WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Output Ports Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Packaged in Thin Shrink Small-Outline Package

description

This 1-bit to 4-bit address register/driver is designed for 1.65-V to 3.6-V V_{CC} operation.

This device is ideal for use in applications in which a single address bus is driving four separate memory locations. The SN74ALVCH162832 can be used as a buffer or a register, depending on the logic level of the select (SEL) input.

When $\overline{SEL}$ is a logic high, the device is in the buffer mode. The outputs follow the inputs and are controlled by the two output-enable ($\overline{OE}$) inputs. Each $\overline{OE}$ controls two groups of seven outputs.

When $\overline{SEL}$ is a logic low, the device is in the register mode. The register is an edge-triggered D-type flip-flop. On the positive transition of the clock (CLK) input, data at the A inputs is stored in the internal registers. $\overline{OE}$ controls operate the same as in the buffer mode.

When $\overline{OE}$ is a logic low, the outputs are in a normal logic state (high or low logic level). When $\overline{OE}$ is a logic high, the outputs are in the high-impedance state.

Neither $\overline{SEL}$ nor $\overline{OE}$ affect the internal operation of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The outputs, which are designed to sink up to 12 mA, include equivalent 26-Ω resistors to reduce overshoot and undershoot.

DGG PACKAGE
(TOP VIEW)

4Y1	1	64	1Y2
3Y1	2	63	2Y2
GND	3	62	GND
2Y1	4	61	3Y2
1Y1	5	60	4Y2
V_{CC}	6	59	V_{CC}
A1	7	58	1Y3
GND	8	57	2Y3
A2	9	56	GND
GND	10	55	3Y3
A3	11	54	4Y3
V_{CC}	12	53	GND
NC	13	52	V_{CC}
GND	14	51	GND
CLK	15	50	1Y4
$\overline{OE1}$	16	49	2Y4
$\overline{OE2}$	17	48	3Y4
$\overline{SEL}$	18	47	4Y4
GND	19	46	GND
A4	20	45	1Y5
A5	21	44	2Y5
V_{CC}	22	43	V_{CC}
GND	23	42	3Y5
A6	24	41	4Y5
GND	25	40	GND
A7	26	39	GND
V_{CC}	27	38	V_{CC}
4Y7	28	37	1Y6
3Y7	29	36	2Y6
GND	30	35	GND
2Y7	31	34	3Y6
1Y7	32	33	4Y6

NC – No internal connection

EPIC and Widebus are trademarks of Texas Instruments Incorporated.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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SN74ALVCH162832
1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER
WITH 3-STATE OUTPUTS

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description (continued)

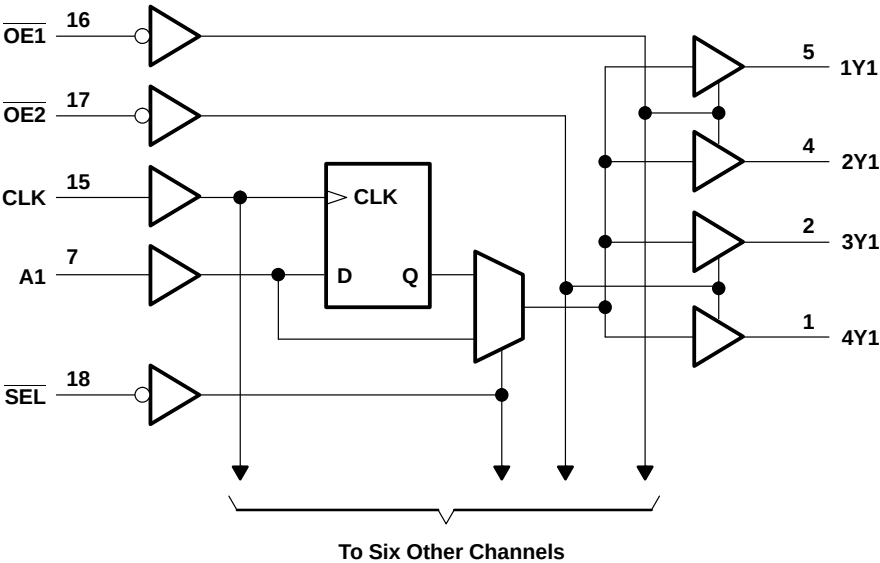
To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH162832 is characterized for operation from -40°C to 85°C .

FUNCTION TABLE				
INPUTS				OUTPUT Y
$\overline{OE}$	$\overline{SEL}$	CLK	A	
H	X	X	X	Z
L	H	X	L	L
L	H	X	H	H
L	L	$\uparrow$	L	L
L	L	$\uparrow$	H	H

logic diagram (positive logic)



SN74ALVCH162832

1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER

WITH 3-STATE OUTPUTS

SCAS588E – MAY 1997 – REVISED FEBRUARY 1999

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3)	106°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	
		$V_{CC} = 2.7$ V to 3.6 V	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	0.7	
		$V_{CC} = 2.7$ V to 3.6 V	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65$ V	–2	mA
		$V_{CC} = 2.3$ V	–6	
		$V_{CC} = 2.7$ V	–8	
		$V_{CC} = 3$ V	–12	
I_{OL}	Low-level output current	$V_{CC} = 1.65$ V	2	mA
		$V_{CC} = 2.3$ V	6	
		$V_{CC} = 2.7$ V	8	
		$V_{CC} = 3$ V	12	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

**1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER
WITH 3-STATE OUTPUTS**

SCAS588E – MAY 1997 – REVISED FEBRUARY 1999

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	4.5			pF
	Data inputs			5			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency	§		150		150		150		MHz
t _w	Pulse duration, CLK high or low	§		3.3		3.3		3.3		ns
t _{su}	Setup time, A data before CLK↑	§		2		2		1.6		ns
t _h	Hold time, A data after CLK↑	§		0.7		0.5		1.1		ns

[§] This information was not available at the time of publication.

SN74ALVCH162832
1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER
WITH 3-STATE OUTPUTS

SCAS588E – MAY 1997 – REVISED FEBRUARY 1999

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	A	Y		†	1.1	4.7	4.8		1.5	4.3	ns
	CLK			†	1	5.3	5.3		1.4	4.7	
	SEL			†	1.1	6	6.2		1.5	4.8	
t _{en}	OE	Y		†	1	5.9	5.9		1.1	5.1	ns
t _{dis}	OE	Y		†	1.4	6.3	5.4		1.6	5.1	ns

† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	All outputs enabled	C _L = 0, f = 10 MHz	†	119	132	pF
		All outputs disabled		†	22	25	

† This information was not available at the time of publication.

SN74ALVCH162832

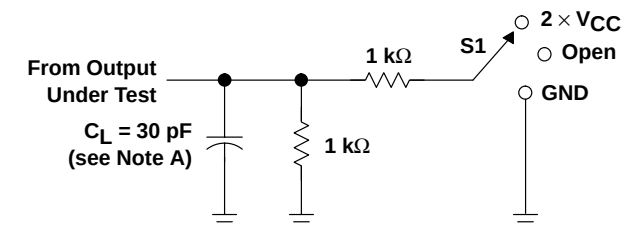
1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER

WITH 3-STATE OUTPUTS

SCAS588E – MAY 1997 – REVISED FEBRUARY 1999

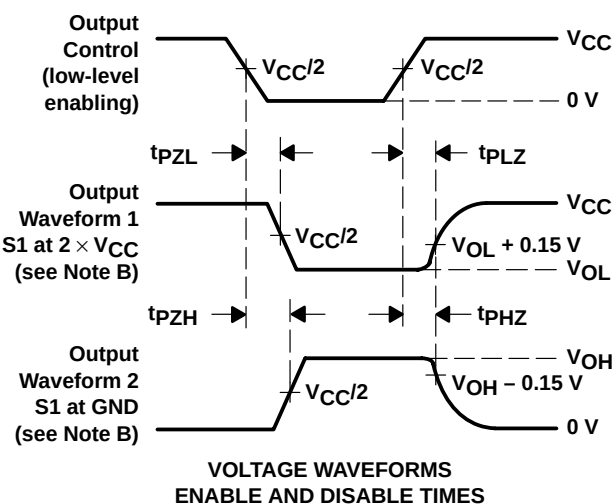
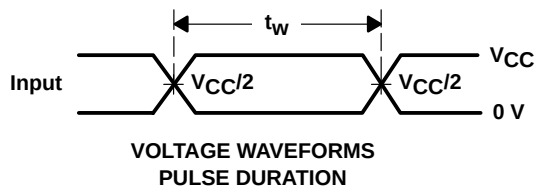
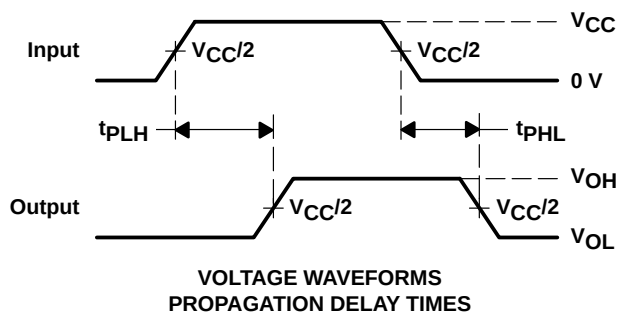
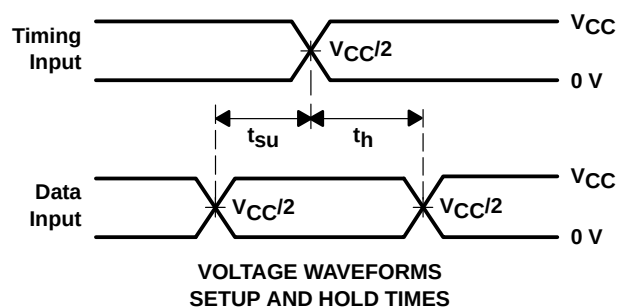
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times$ V_{CC}
t_{PHZ}/t_{PHL}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH162832

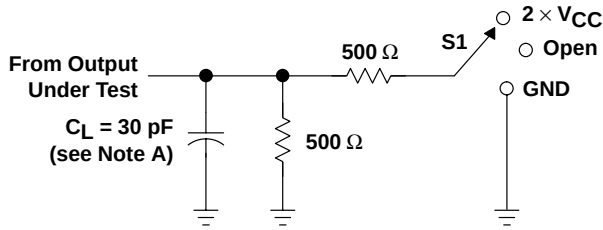
1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER

WITH 3-STATE OUTPUTS

SCAS588E – MAY 1997 – REVISED FEBRUARY 1999

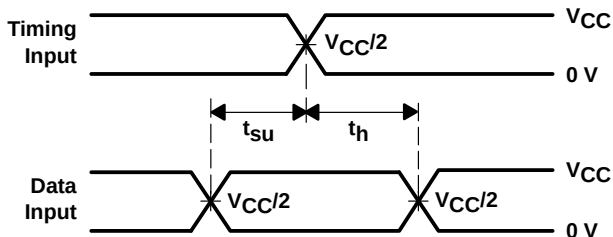
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

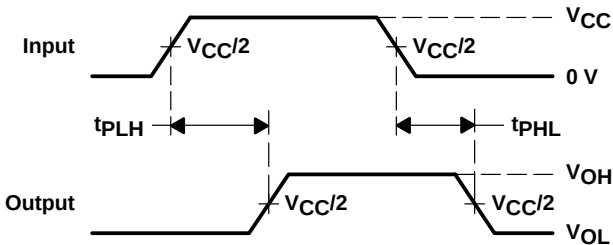


LOAD CIRCUIT

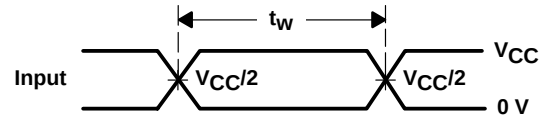
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



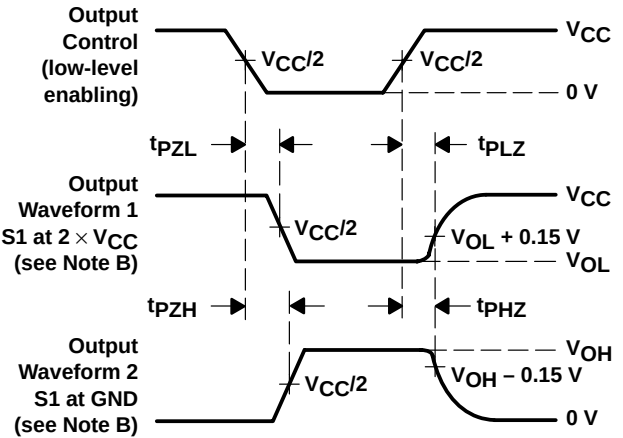
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES: A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
- D. The outputs are measured one at a time with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

SN74ALVCH162832

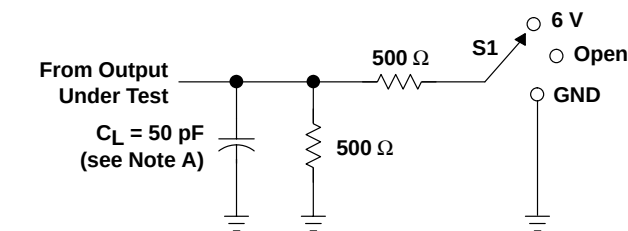
1-BIT TO 4-BIT ADDRESS REGISTER/DRIVER

WITH 3-STATE OUTPUTS

SCAS588E – MAY 1997 – REVISED FEBRUARY 1999

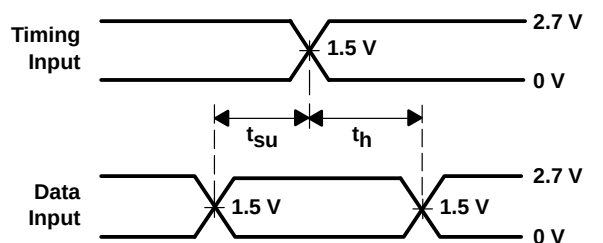
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

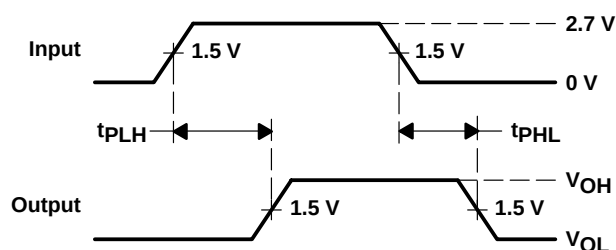


LOAD CIRCUIT

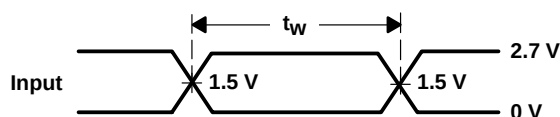
TEST	S1
t_{pd}	Open
t_{pLZ}/t_{pZL}	6 V
t_{pHZ}/t_{pZH}	GND



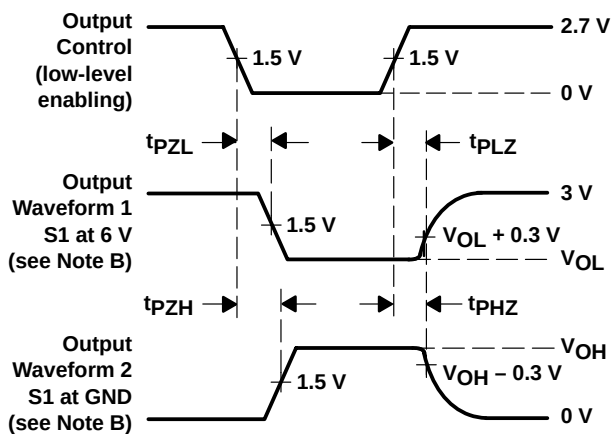
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{pLZ} and t_{pHZ} are the same as t_{dis} .
 - t_{pZL} and t_{pZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVC162834

18-BIT UNIVERSAL BUS DRIVER WITH 3-STATE OUTPUTS

SCES172A – DECEMBER 1998 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- Outputs Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Package Options Include Plastic Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages

description

This 18-bit universal bus driver is designed for 1.65-V to 3.6-V V_{CC} operation.

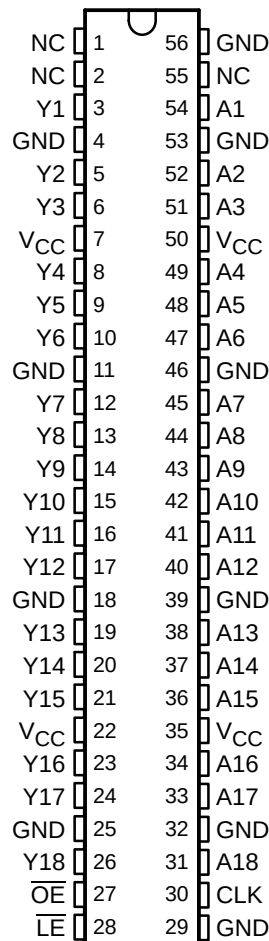
Data flow from A to Y is controlled by the output-enable ($\overline{OE}$) input. The device operates in the transparent mode when the latch-enable ($\overline{LE}$) input is low. The A data is latched if the clock (CLK) input is held at a high or low logic level. If $\overline{LE}$ is high, the A data is stored in the latch/flip-flop on the low-to-high transition of CLK. When $\overline{OE}$ is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The outputs, which are designed to sink up to 12 mA, include equivalent 26-Ω resistors to reduce overshoot and undershoot.

The SN74ALVC162834 is characterized for operation from –40°C to 85°C.

DGG, DGV, OR DL PACKAGE
(TOP VIEW)



NC – No internal connection

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SN74ALVC162834
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WITH 3-STATE OUTPUTS

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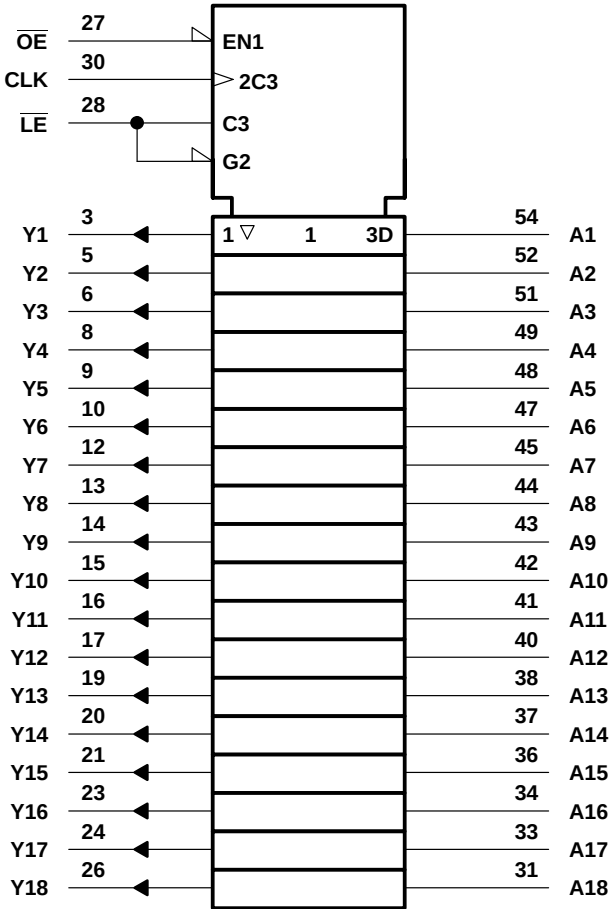
FUNCTION TABLE

INPUTS				OUTPUT Y
OE	LE	CLK	A	
H	X	X	X	Z
L	L	X	L	L
L	L	X	H	H
L	H	↑	L	L
L	H	↑	H	H
L	H	H	X	Y ₀ [†]
L	H	L	X	Y ₀ [‡]

† Output level before the indicated steady-state input conditions were established, provided that CLK is high before LE goes high

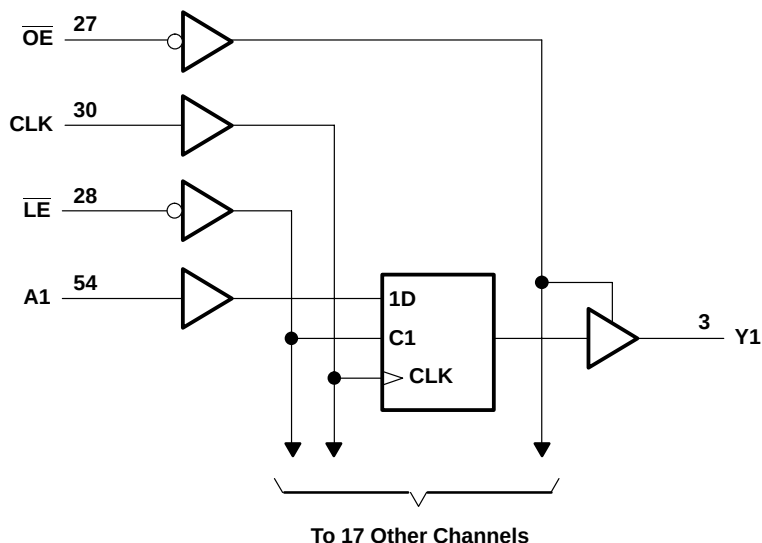
‡ Output level before the indicated steady-state input conditions were established

logic symbols



§ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3):	
DGG package	81°C/W
DGV package	86°C/W
DL package	74°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–2	mA
		$V_{CC} = 2.3 \text{ V}$	–6	
		$V_{CC} = 2.7 \text{ V}$	–8	
		$V_{CC} = 3 \text{ V}$	–12	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	2	mA
		$V_{CC} = 2.3 \text{ V}$	6	
		$V_{CC} = 2.7 \text{ V}$	8	
		$V_{CC} = 3 \text{ V}$	12	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	4			pF
	Data inputs			5.5			
C _o	Outputs	V _O = V _{CC} or GND	3.3 V	7			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

				V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
				MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency			‡		150		150		150		MHz
t _w	Pulse duration	LE low		‡		3.3		3.3		3.3		ns
		CLK high or low		‡		3.3		3.3		3.3		
t _{su}	Setup time	Data before CLK↑		‡		2.1		2.1		1.7		ns
		Data before LE↑	CLK high	‡		2.3		2.3		1.9		
			CLK low	‡		1.9		1.9		1.5		
t _h	Hold time	Data after CLK↑		‡		0.6		0.6		0.7		ns
		Data after LE↑	CLK high or low	‡		0.8		0.8		0.9		

‡ This information was not available at the time of publication.



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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	A	Y	†		1 5.2		5		1 4.2		ns
	$\overline{\text{LE}}$		†		1.3 6		6.8		1.3 5.8		
	CLK		†		1.4 6.8		6.1		1.4 5.4		
t _{en}	$\overline{\text{OE}}$	Y	†		1.4 6.3		6.5		1.5 5.9		ns
t _{dis}	$\overline{\text{OE}}$	Y	†		1 4.4		5.2		1.8 5		ns

† This information was not available at the time of publication.

switching characteristics from 0°C to 65°C, C_L = 50 pF

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 3.3 V ± 0.15 V		UNIT
			MIN	MAX	
t _{pd}	A	Y	1.4	3.9	ns
	$\overline{LE}$		1.8	5.5	
	CLK		1.8	5.2	

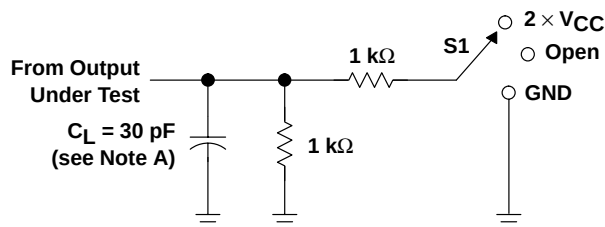
operating characteristics, T_A = 25°C

PARAMETER		TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
			TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	C _L = 0, f = 10 MHz	†	38	41	pF
	Outputs enabled		†	13	15	

† This information was not available at the time of publication.

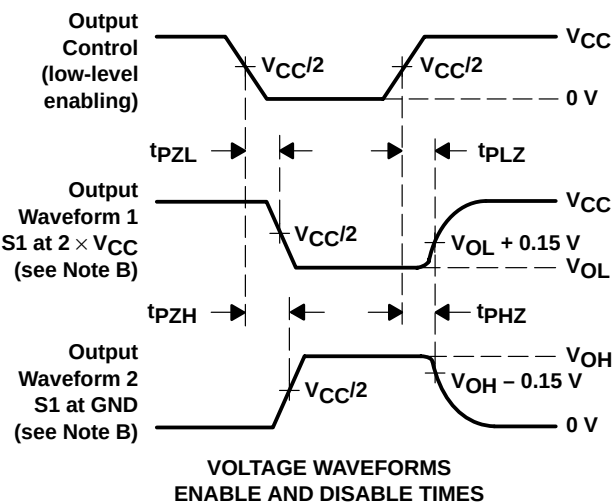
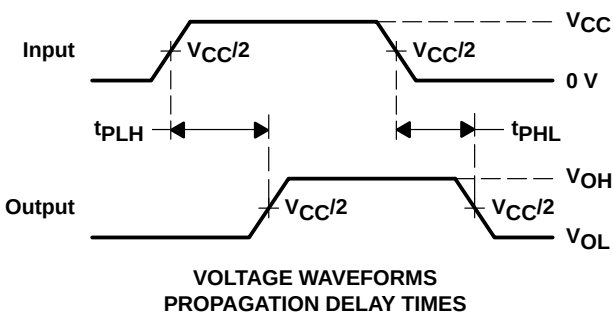
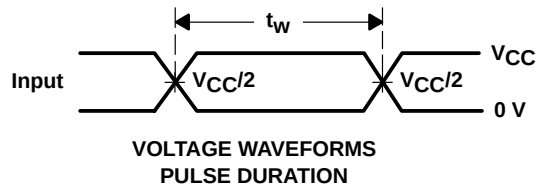
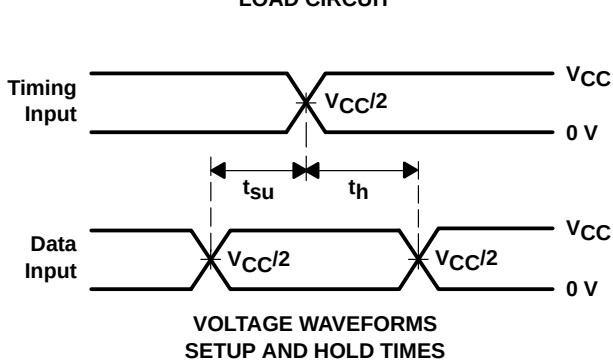
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVC162834

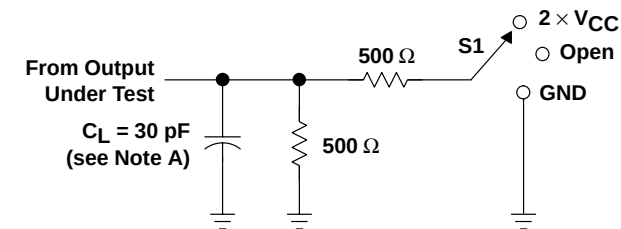
18-BIT UNIVERSAL BUS DRIVER

WITH 3-STATE OUTPUTS

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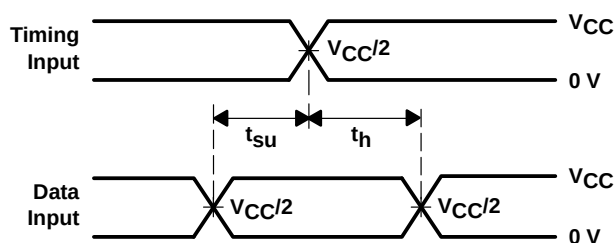
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

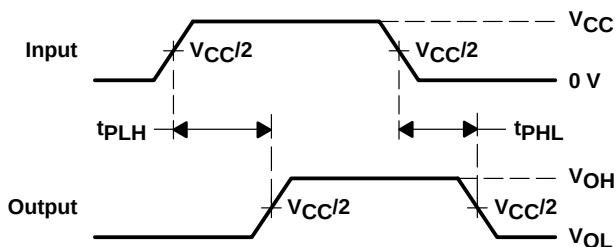


LOAD CIRCUIT

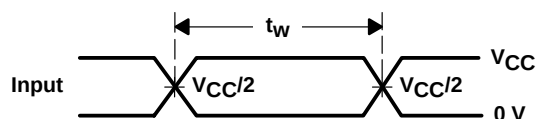
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



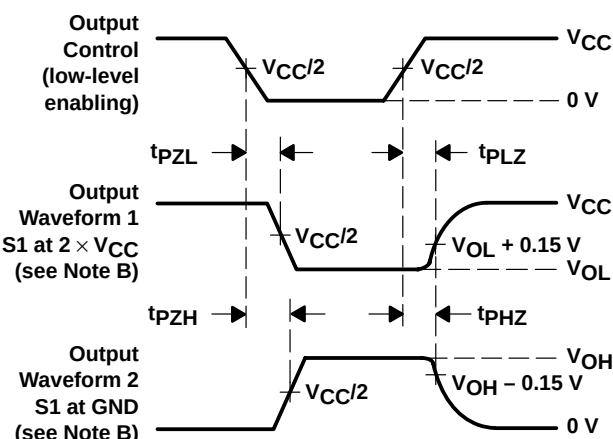
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



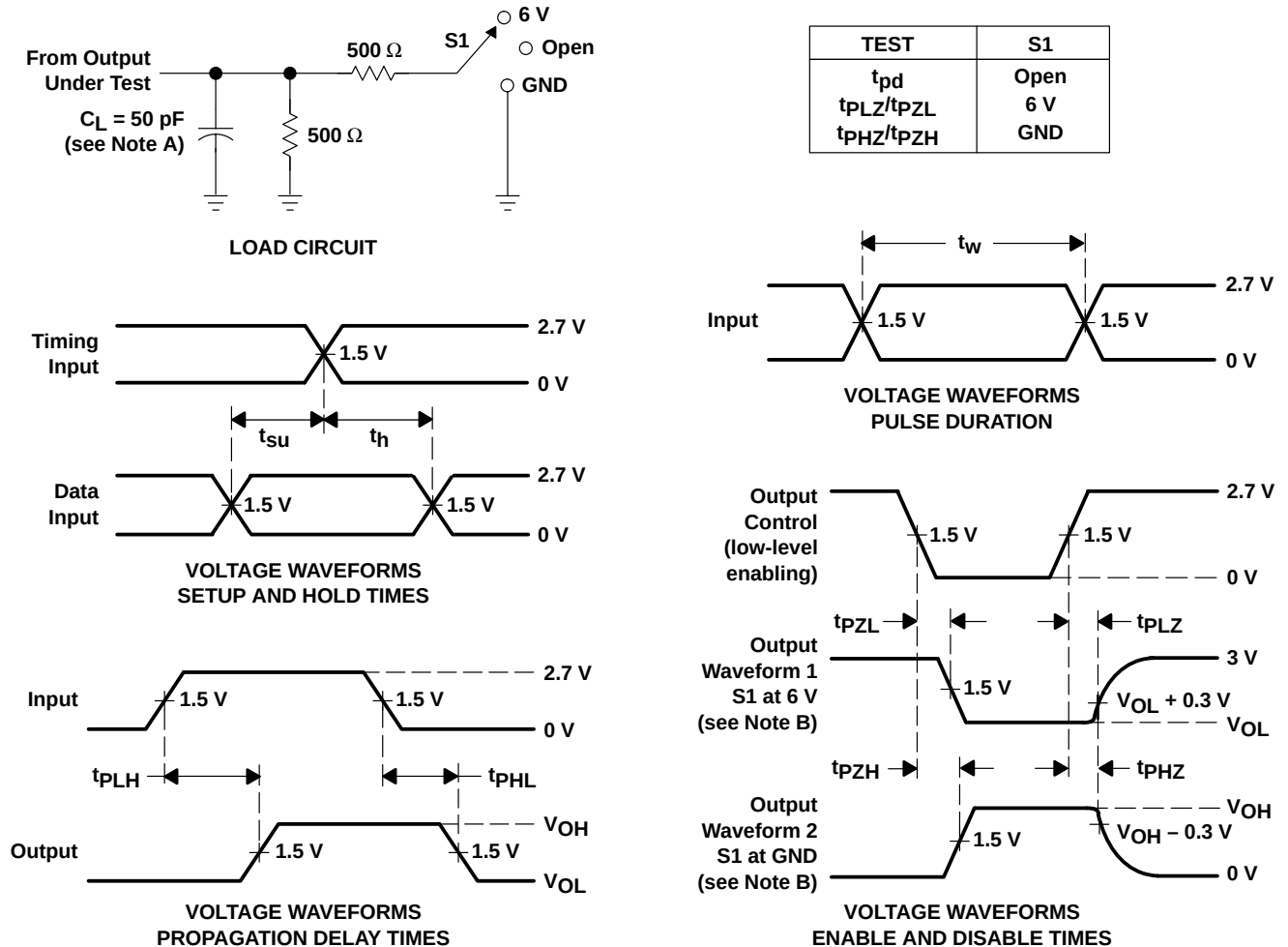
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{pZL} and t_{pZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVC162835 18-BIT UNIVERSAL BUS DRIVER WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Ideal for Use in PC100 Register DIMM Revision 1.1
- Output Port Has Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Package Options Include Plastic Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages

description

This 18-bit universal bus driver is designed for 1.65-V to 3.6-V V_{CC} operation.

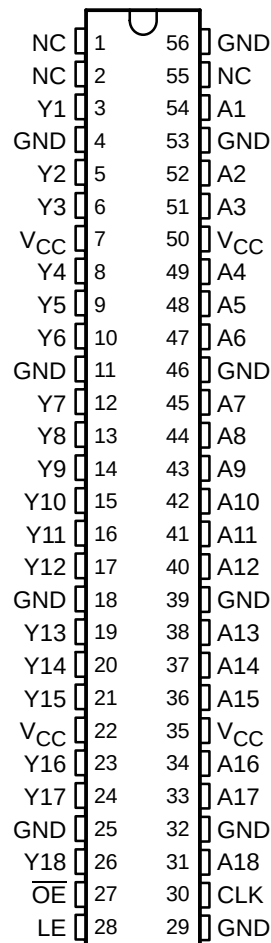
Data flow from A to Y is controlled by the output-enable ($\overline{OE}$) input. The device operates in the transparent mode when the latch-enable (LE) input is high. When LE is low, the A data is latched if the clock (CLK) input is held at a high or low logic level. If LE is low, the A data is stored in the latch/flip-flop on the low-to-high transition of CLK. When $\overline{OE}$ is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The output port includes equivalent 26-Ω series resistors to reduce overshoot and undershoot.

The SN74ALVC162835 is characterized for operation from –40°C to 85°C.

DGG, DGV, OR DL PACKAGE (TOP VIEW)



NC – No internal connection

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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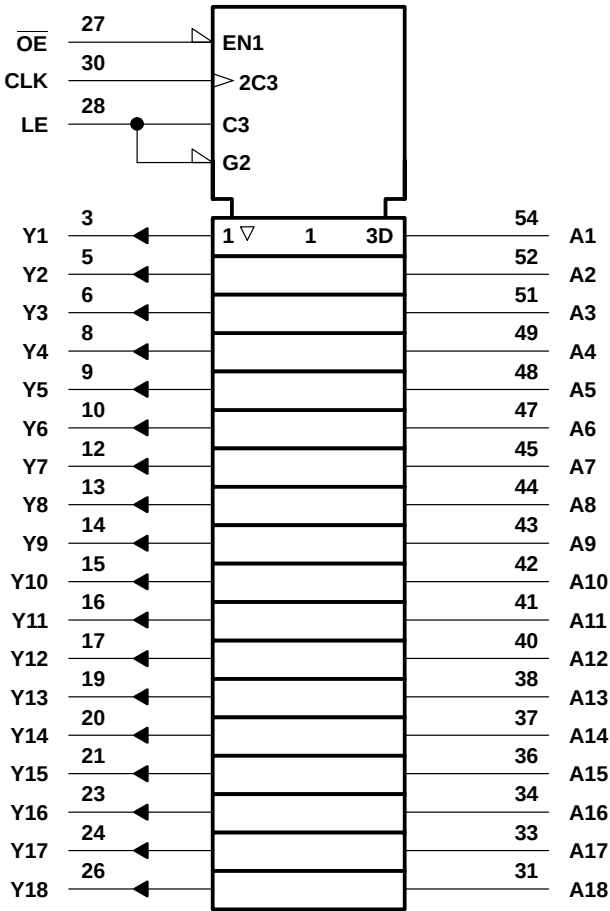
SCES126E – FEBRUARY 1998 – REVISED FEBRUARY 1999

FUNCTION TABLE

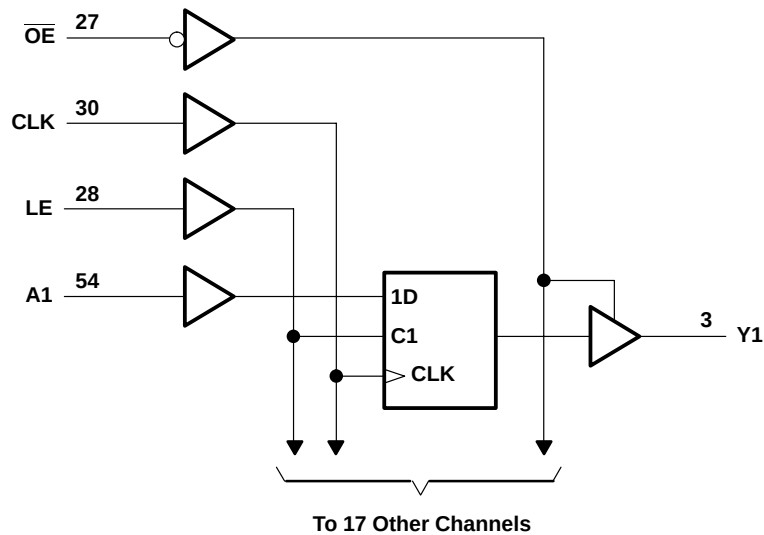
INPUTS				OUTPUT Y
OE	LE	CLK	A	
H	X	X	X	Z
L	H	X	L	L
L	H	X	H	H
L	L	↑	L	L
L	L	↑	H	H
L	L	L or H	X	Y ₀ [†]

† Output level before the indicated steady-state input conditions were established

logic symbol[‡]



[‡] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



Supply voltage range, V_{CC}		-0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)		-0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)		-0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)		-50 mA
Output clamp current, I_{OK} ($V_O < 0$)		-50 mA
Continuous output current, I_O		± 50 mA
Continuous current through each V_{CC} or GND		± 100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package		81°C/W
DGV package		86°C/W
DL package		74°C/W
Storage temperature range, T_{Stg}		-65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–2	mA
		$V_{CC} = 2.3 \text{ V}$	–6	
		$V_{CC} = 2.7 \text{ V}$	–8	
		$V_{CC} = 3 \text{ V}$	–12	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	2	mA
		$V_{CC} = 2.3 \text{ V}$	6	
		$V_{CC} = 2.7 \text{ V}$	8	
		$V_{CC} = 3 \text{ V}$	12	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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18-BIT UNIVERSAL BUS DRIVER
WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3.5			pF
	Data inputs			5			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

				V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
				MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency			‡		150		150		150		MHz
t _w	Pulse duration	LE high		‡		3.3		3.3		3.3		ns
		CLK high or low		‡		3.3		3.3		3.3		
t _{su}	Setup time	Data before CLK↑		‡		2.2		2.1		1.7		ns
		Data before LE↓	CLK high	‡		1.9		1.6		1.5		
			CLK low	‡		1.3		1.1		1		
t _h	Hold time	Data after CLK↑		‡		0.6		0.6		0.7		ns
		Data after LE↓	CLK high or low	‡		1.4		1.7		1.4		

‡ This information was not available at the time of publication.



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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	A	Y		†	1	5	5		1	4.2	ns
	LE			†	1.3	5.9	5.8		1.3	5.1	
	CLK			†	1.4	6.3	6.1		1.4	5.4	
t _{en}	OE	Y		†	1.4	6.3	6.5		1.1	5.5	ns
t _{dis}	OE	Y		†	1	4.9	4.9		1.3	4.5	ns

† This information was not available at the time of publication.

switching characteristics from 0°C to 85°C, C_L = 0 pF

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 3.3 V ± 0.15 V		UNIT
			MIN	MAX	
t _{pd} ‡	A	Y	0.9	2	ns
	CLK	Y	1.4	2.9	ns

‡ Texas Instruments SPICE simulation data

switching characteristics from 0°C to 65°C, C_L = 50 pF

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 3.3 V ± 0.15 V		UNIT
			MIN	MAX	
t _{pd}	A	Y	1	4	ns
	CLK	Y	1.9	5	ns

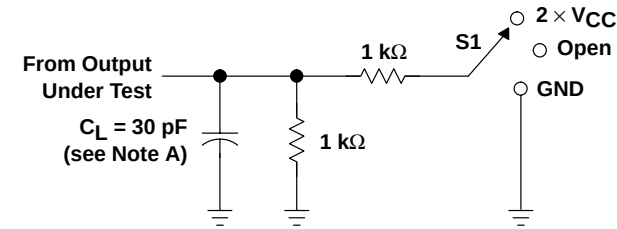
operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd} Power dissipation capacitance	Outputs enabled	C _L = 0, f = 10 MHz		†	35.5	40	pF
	Outputs disabled			†	12.5	14	

† This information was not available at the time of publication.

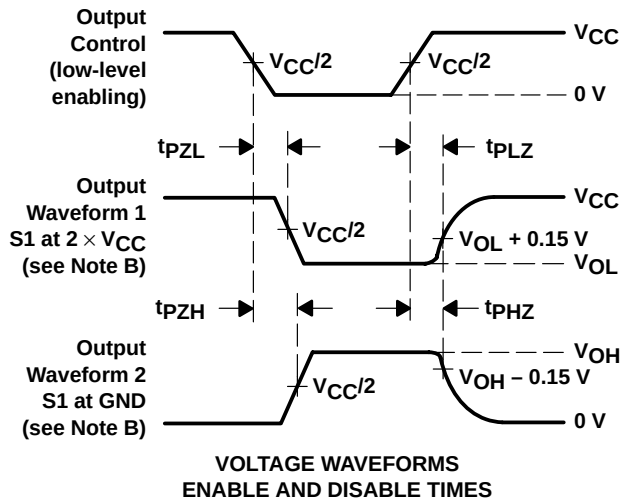
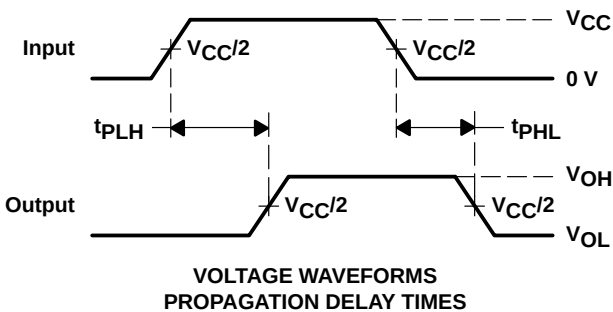
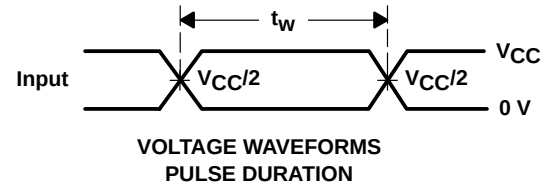
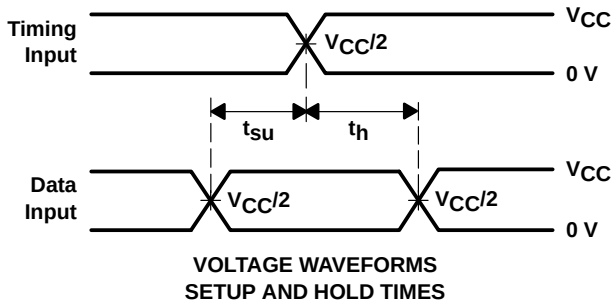


PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	$2 \times V_{CC}$
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

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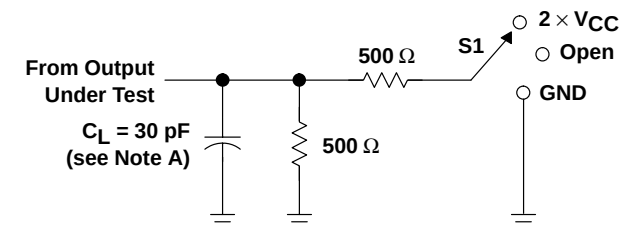
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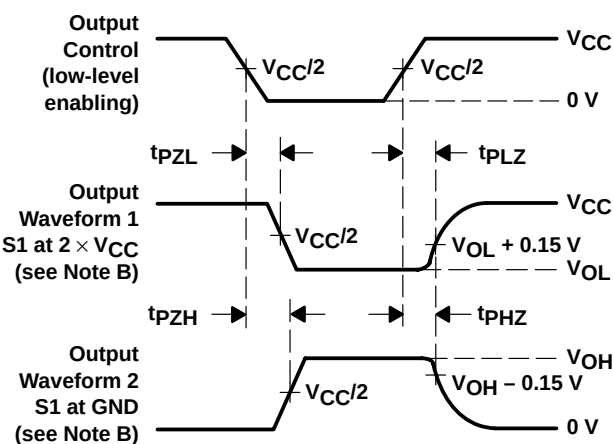
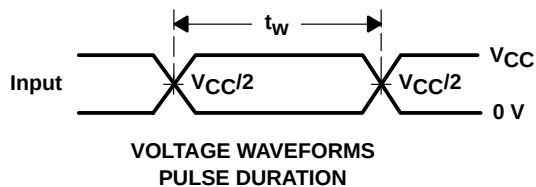
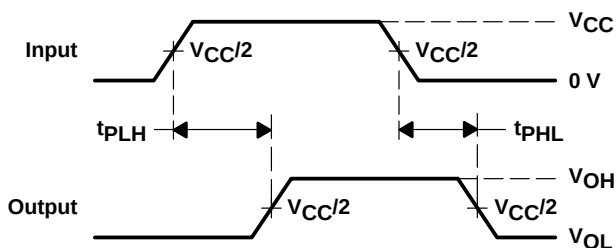
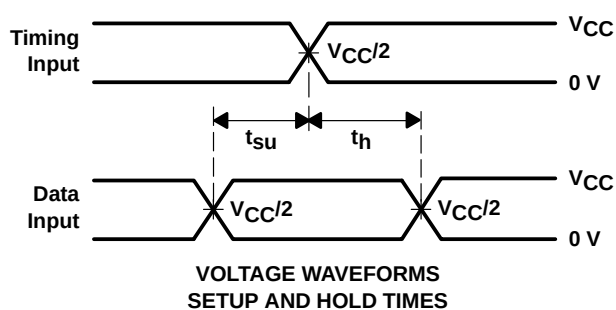
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	$2 \times V_{CC}$
t_{PHZ}/t_{PHL}	GND

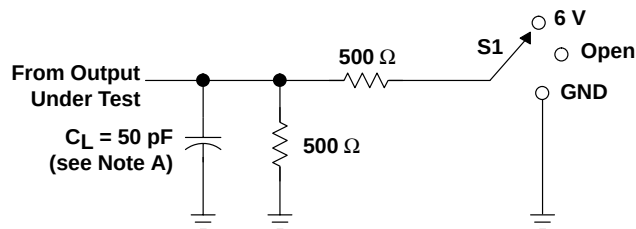


- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

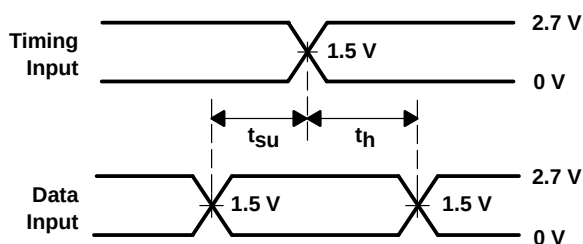
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

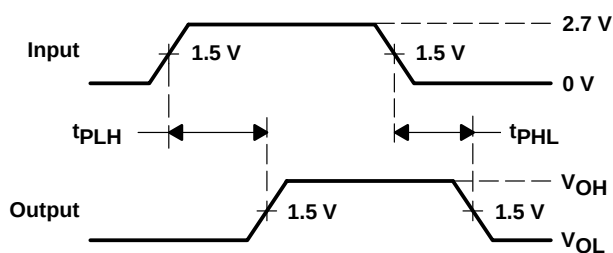


LOAD CIRCUIT

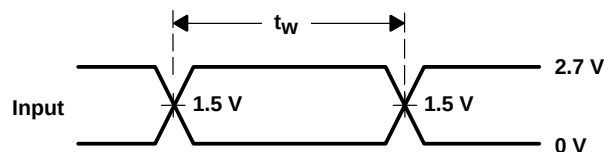
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



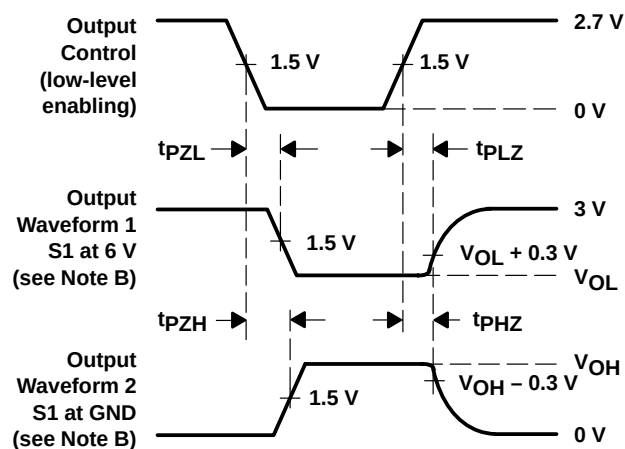
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

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TYPICAL CHARACTERISTICS

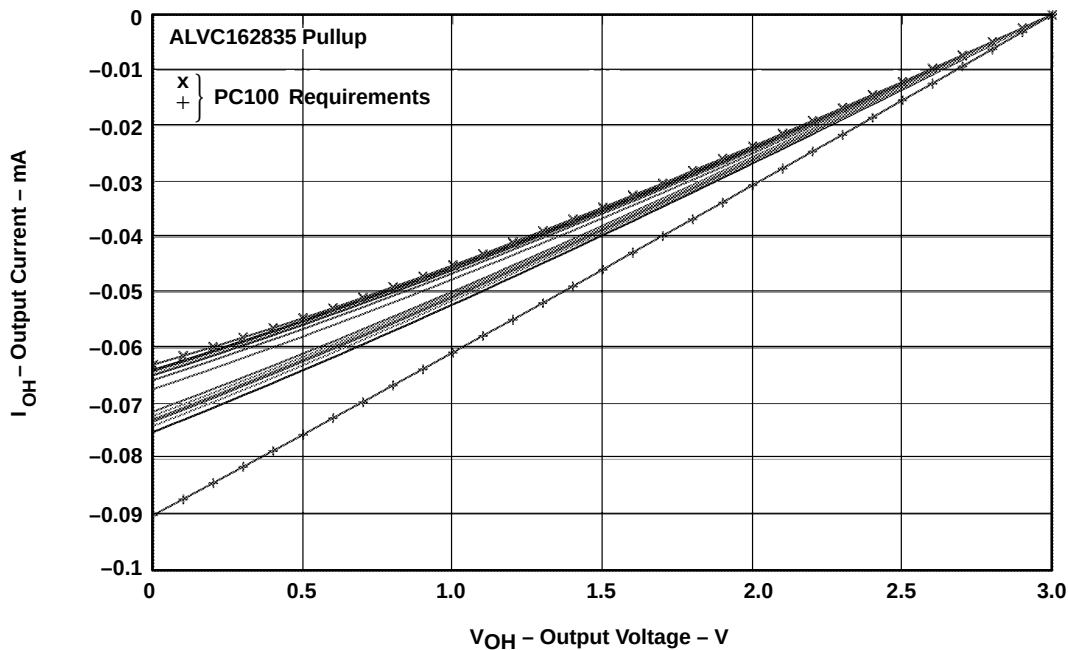


Figure 4. IV Characteristics – Pullup

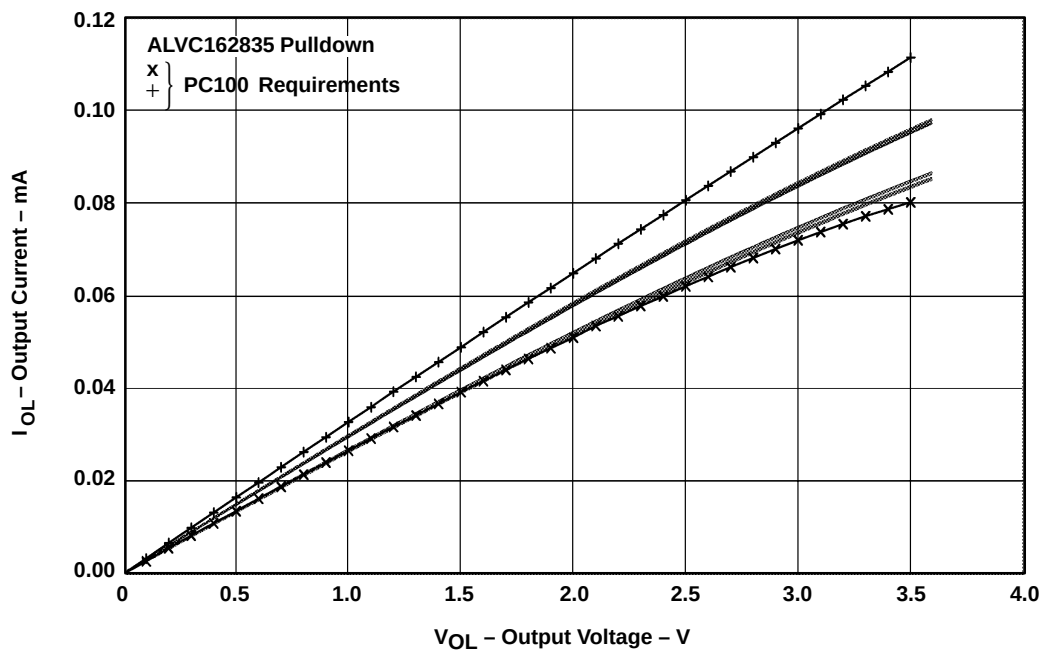


Figure 5. IV Characteristics – Pulldown



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- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Output Port Has Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages

description

This 18-bit universal bus driver is designed for 1.65-V to 3.6-V V_{CC} operation.

Data flow from A to Y is controlled by the output-enable ($\overline{OE}$) input. The device operates in the transparent mode when the latch-enable (LE) input is high. When LE is low, the A data is latched if the clock (CLK) input is held at a high or low logic level. If LE is low, the A data is stored in the latch/flip-flop on the low-to-high transition of CLK. When $\overline{OE}$ is high, the outputs are in the high-impedance state.

The output port includes equivalent 26-Ω series resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH162835 is characterized for operation from –40°C to 85°C.

DGG, DGV, OR DL PACKAGE (TOP VIEW)

NC	1	56	GND
NC	2	55	NC
Y1	3	54	A1
GND	4	53	GND
Y2	5	52	A2
Y3	6	51	A3
V_{CC}	7	50	V_{CC}
Y4	8	49	A4
Y5	9	48	A5
Y6	10	47	A6
GND	11	46	GND
Y7	12	45	A7
Y8	13	44	A8
Y9	14	43	A9
Y10	15	42	A10
Y11	16	41	A11
Y12	17	40	A12
GND	18	39	GND
Y13	19	38	A13
Y14	20	37	A14
Y15	21	36	A15
V_{CC}	22	35	V_{CC}
Y16	23	34	A16
Y17	24	33	A17
GND	25	32	GND
Y18	26	31	A18
$\overline{OE}$	27	30	CLK
LE	28	29	GND

NC – No internal connection

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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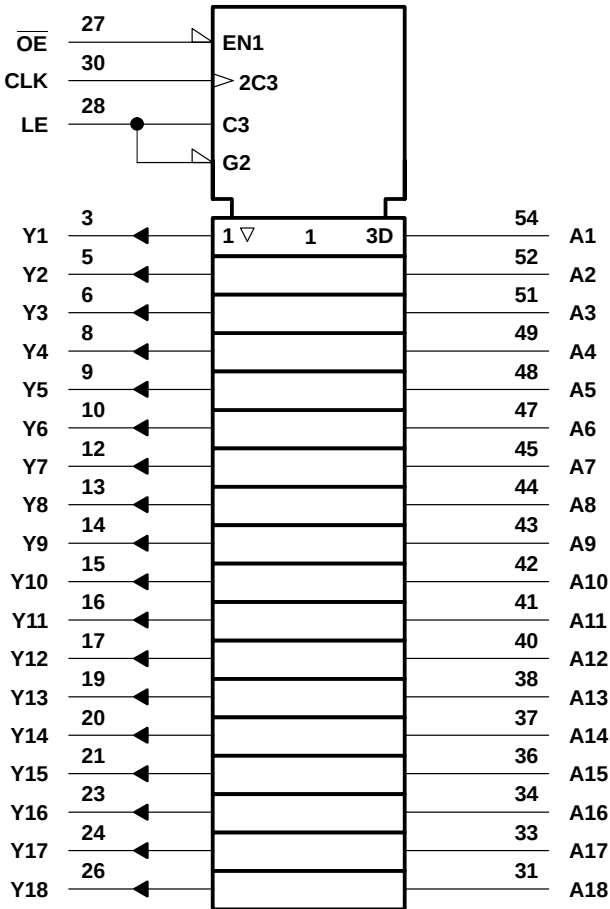
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FUNCTION TABLE

INPUTS				OUTPUT Y
OE	LE	CLK	A	
H	X	X	X	Z
L	H	X	L	L
L	H	X	H	H
L	L	↑	L	L
L	L	↑	H	H
L	L	L or H	X	Y ₀ [†]

† Output level before the indicated steady-state input conditions were established

logic symbol[‡]



[‡] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Package thermal impedance, θ_{JA} (see Note 3):	DGG package	81°C/W
	DGV package	86°C/W
	DL package	74°C/W

Storage temperature range, T_{stg} -65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. This value is limited to 4.6 V maximum.

3. The package thermal impedance is calculated in accordance with JESD 51.

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–2	mA
		$V_{CC} = 2.3 \text{ V}$	–6	
		$V_{CC} = 2.7 \text{ V}$	–8	
		$V_{CC} = 3 \text{ V}$	–12	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	2	mA
		$V_{CC} = 2.3 \text{ V}$	6	
		$V_{CC} = 2.7 \text{ V}$	8	
		$V_{CC} = 3 \text{ V}$	12	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3.5			pF
	Data inputs			6			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.



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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

				V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
				MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency			†		150		150		150		MHz
t _w	Pulse duration	LE high		†		3.3		3.3		3.3		ns
		CLK high or low		†		3.3		3.3		3.3		
t _{su}	Setup time	Data before CLK↑		†		2.2		2.1		1.7		ns
		Data before LE↓	CLK high	†		1.9		1.6		1.5		
			CLK low	†		1.3		1.1		1		
t _h	Hold time	Data after CLK↑		†		0.6		0.6		0.7		ns
		Data after LE↓	CLK high or low	†		1.4		1.7		1.4		

† This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	A	Y	†		1 5		5		1 4.2		ns
	LE		†		1.3 5.9		5.8		1.3 5.1		
	CLK		†		1.4 6.3		6.1		1.4 5.4		
t _{en}	OE	Y	†		1.4 6.3		6.5		1.1 5.5		ns
t _{dis}	OE	Y	†		1 4.7		4.9		1.3 4.5		ns

† This information was not available at the time of publication.

switching characteristics from 0°C to 65°C, C_L = 50 pF

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 3.3 V ± 0.15 V		UNIT
			MIN	MAX	
t _{pd}	CLK	Y	1.9	5	ns

operating characteristics, T_A = 25°C

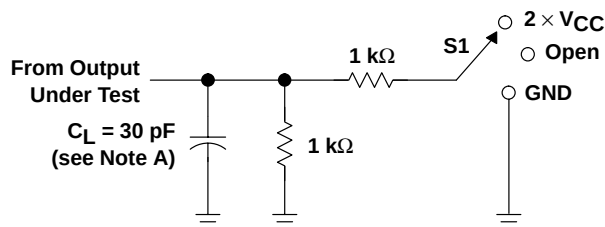
PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 0, f = 10 MHz	†	36	41	pF
		Outputs disabled		†	12.5	14	

† This information was not available at the time of publication.



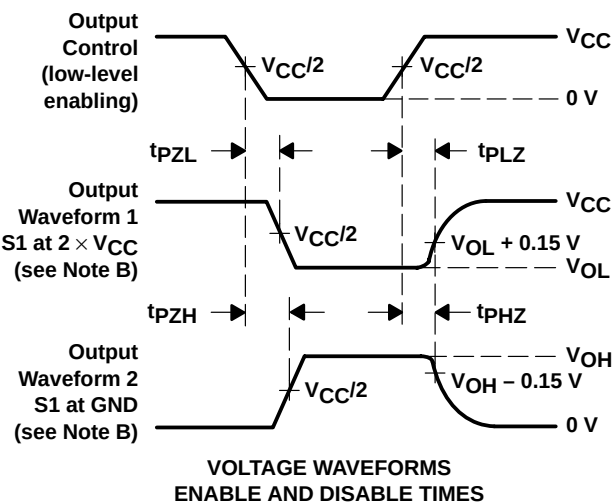
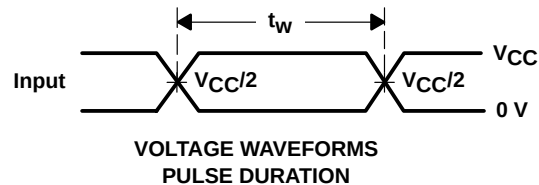
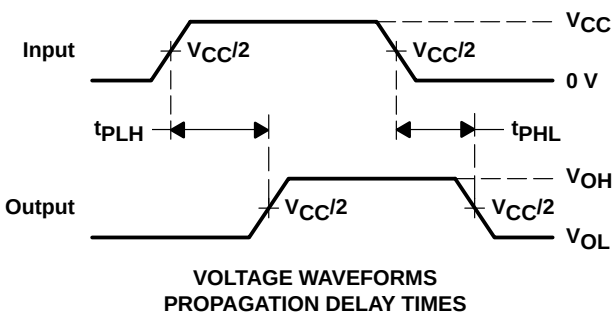
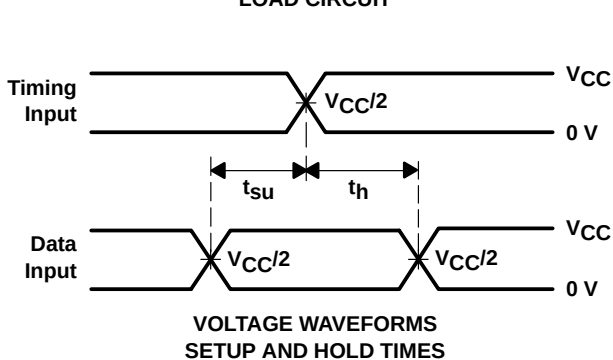
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH162835

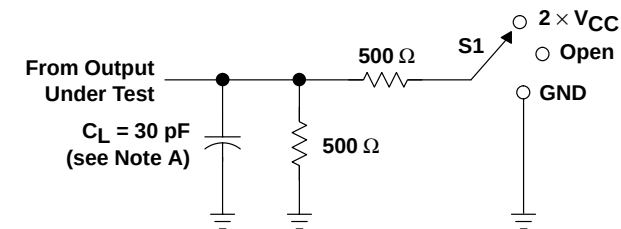
18-BIT UNIVERSAL BUS DRIVER

WITH 3-STATE OUTPUTS

SCES121D – JULY 1997 – REVISED FEBRUARY 1999

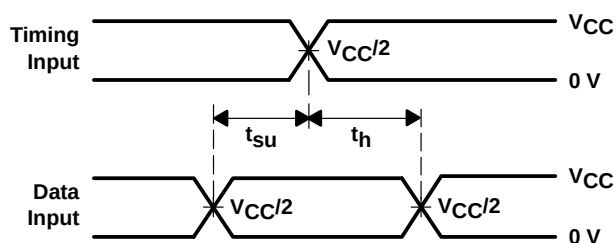
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

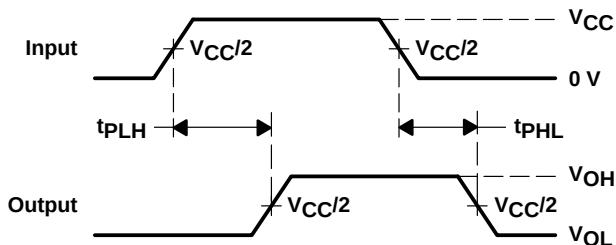


LOAD CIRCUIT

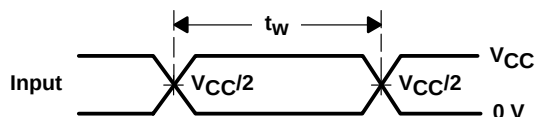
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



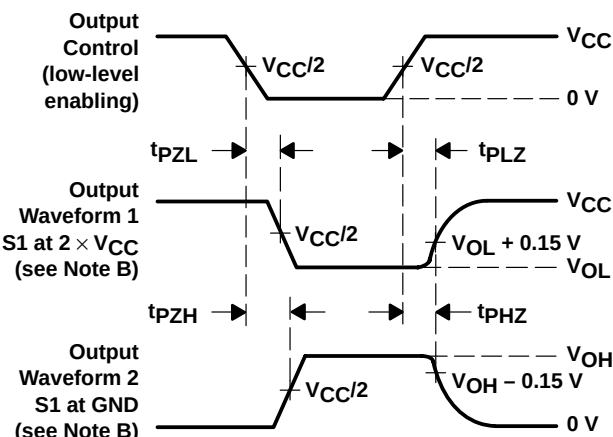
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



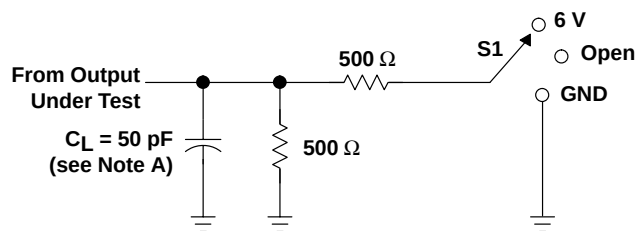
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

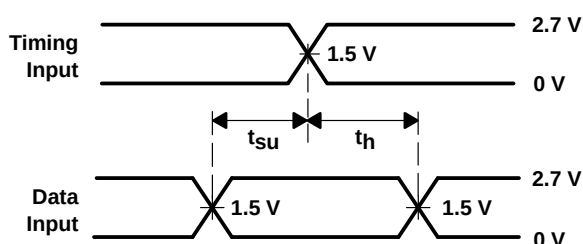
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

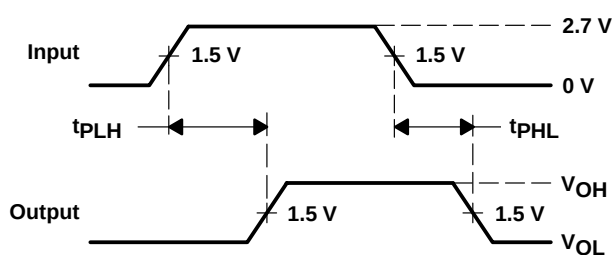


LOAD CIRCUIT

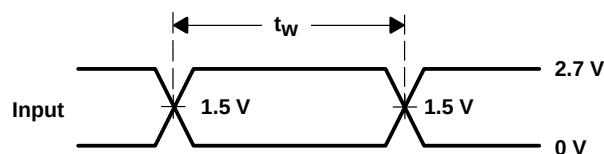
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



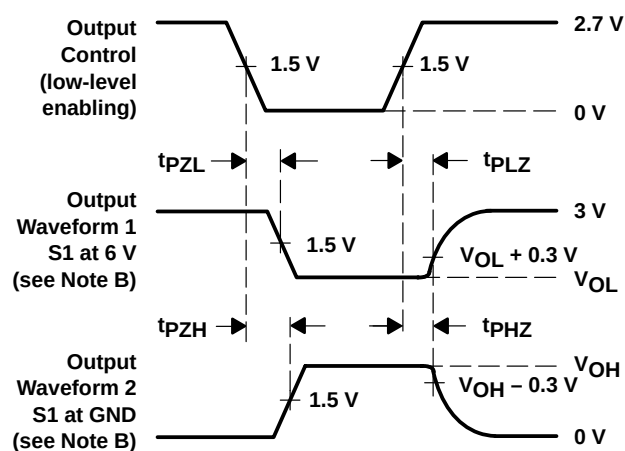
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVC162836

20-BIT UNIVERSAL BUS DRIVER WITH 3-STATE OUTPUTS

SCES129B – MARCH 1998 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- Output Port Has Equivalent 26- Ω Series Resistors, So No External Resistors Are Required
- Designed to Comply With JEDEC 168-Pin and 200-Pin SDRAM Buffered DIMM Specification
- Package Options Include Plastic Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages

description

This 20-bit universal bus driver is designed for 1.65-V to 3.6-V V_{CC} operation.

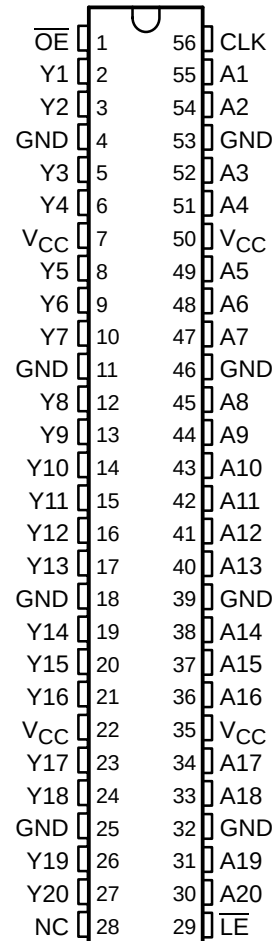
Data flow from *A* to *Y* is controlled by the output-enable ($\overline{OE}$) input. The device operates in the transparent mode when the latch-enable ($\overline{LE}$) input is low. When $\overline{LE}$ is high, the *A* data is latched if the clock (*CLK*) input is held at a high or low logic level. If $\overline{LE}$ is high, the *A* data is stored in the latch/flip-flop on the low-to-high transition of *CLK*. When $\overline{OE}$ is high, the outputs are in the high-impedance state.

The output port includes equivalent 26- Ω series resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74ALVC162836 is characterized for operation from -40°C to 85°C .

DGG, DGV, OR DL PACKAGE (TOP VIEW)



NC – No internal connection

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



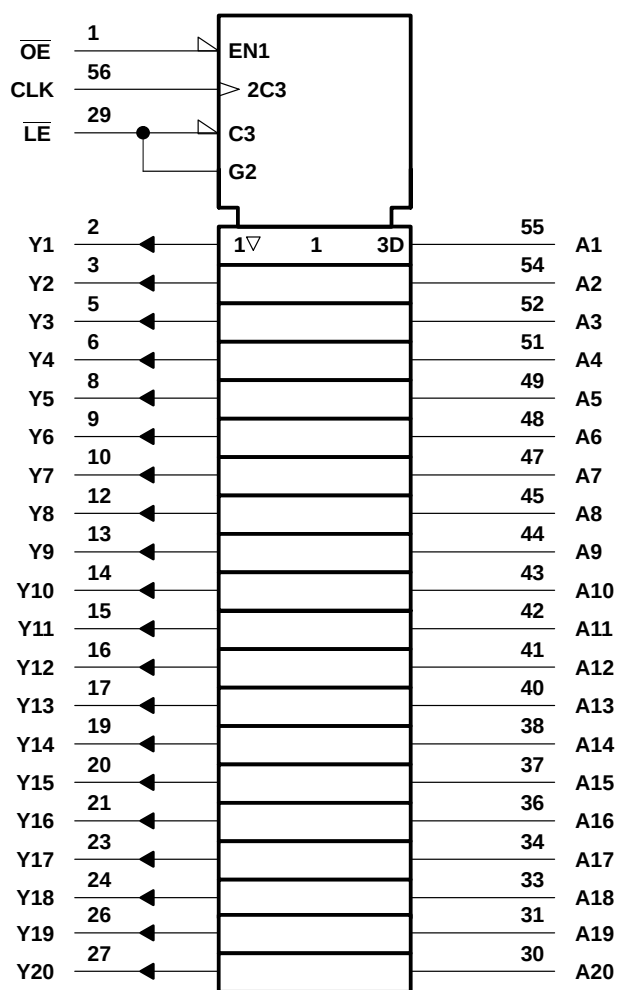
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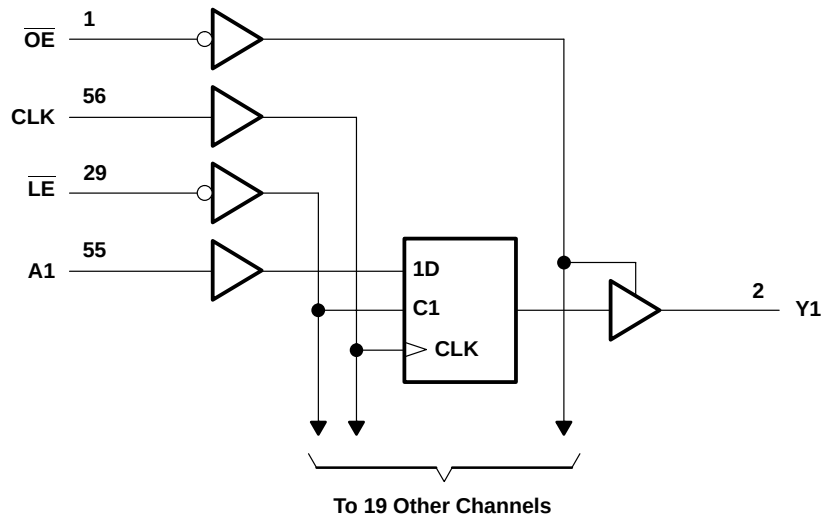
SCES129B – MARCH 1998 – REVISED FEBRUARY 1999

INPUTS				OUTPUT Y
OE	LE	CLK	A	
H	X	X	X	Z
L	L	X	L	L
L	L	X	H	H
L	H	↑	L	L
L	H	↑	H	H
L	H	L or H	X	Y ₀ [†]

logic symbol‡



logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3):	
DGG package	81°C/W
DGV package	86°C/W
DL package	74°C/W
Storage temperature range, T_{Stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–2	mA
		$V_{CC} = 2.3 \text{ V}$	–6	
		$V_{CC} = 2.7 \text{ V}$	–8	
		$V_{CC} = 3 \text{ V}$	–12	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	2	mA
		$V_{CC} = 2.3 \text{ V}$	6	
		$V_{CC} = 2.7 \text{ V}$	8	
		$V_{CC} = 3 \text{ V}$	12	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	5			pF
	Data inputs			5.5			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

				V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
				MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency			‡		150		150		150		MHz
t _w	Pulse duration	LE low		‡		3.3		3.3		3.3		ns
		CLK high or low		‡		3.3		3.3		3.3		
t _{su}	Setup time	Data before CLK↑		‡		1.4		1.7		1.5		ns
		Data before LE↑	CLK high	‡		1.2		1.6		1.3		
			CLK low	‡		1.4		1.5		1.2		
t _h	Hold time	Data after CLK↑		‡		0.9		0.9		0.9		ns
		Data after LE↑	CLK high or low	‡		1.1		1.1		1.1		

‡ This information was not available at the time of publication.



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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	A	Y	†		1	4.4	4.6		1.2	4	ns
	$\overline{\text{LE}}$		†		1.1	5.8	6.1		1.4	5.1	
	CLK		†		1	5.2	5.5		1.1	5	
t _{en}	$\overline{\text{OE}}$	Y	†		1.1	6.4	6.5		1.2	5.5	ns
t _{dis}	$\overline{\text{OE}}$	Y	†		1	4.7	5.2		1.7	5.1	ns

† This information was not available at the time of publication.

switching characteristics from 0°C to 65°C, C_L = 50 pF

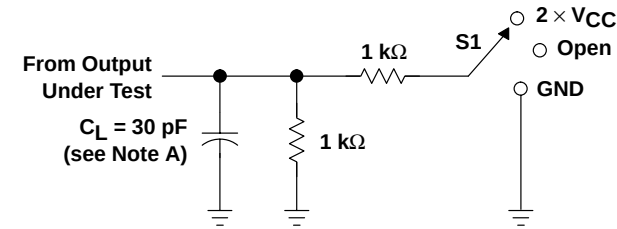
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 3.3 V ± 0.15 V		UNIT
			MIN	MAX	
t _{pd}	A	Y	1	4	ns
	CLK	Y	1.7	4.5	ns

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 0, f = 10 MHz	†	31	36	pF
		Outputs disabled		†	7	11	

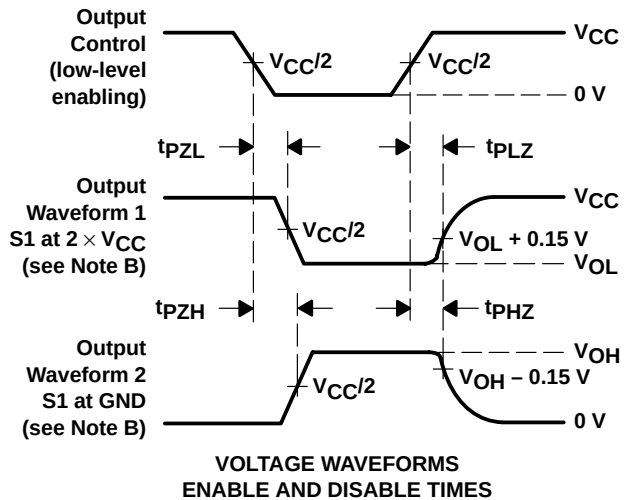
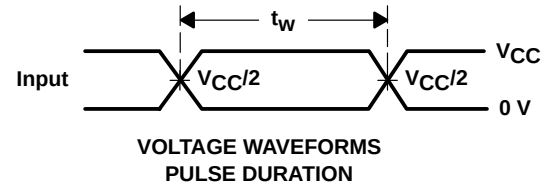
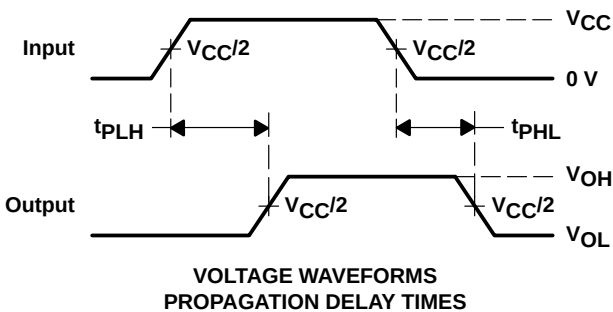
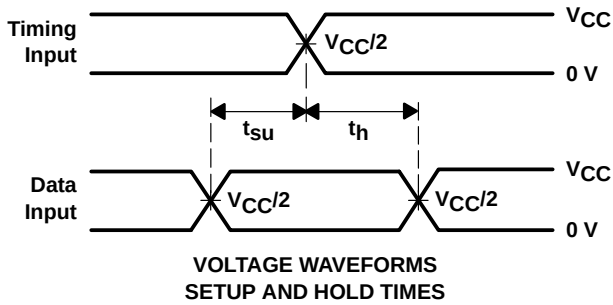
† This information was not available at the time of publication.

PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8 \text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVC162836

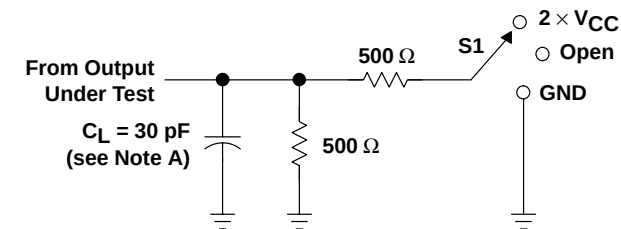
20-BIT UNIVERSAL BUS DRIVER

WITH 3-STATE OUTPUTS

SCES129B – MARCH 1998 – REVISED FEBRUARY 1999

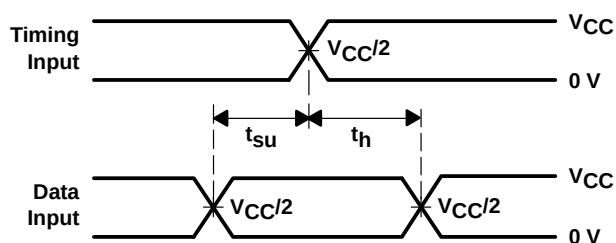
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

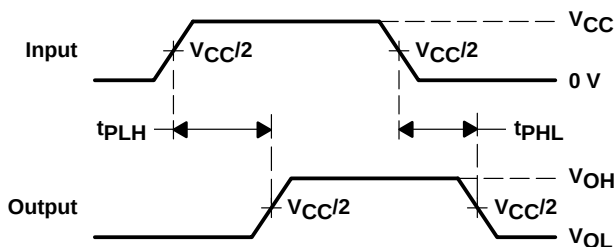


LOAD CIRCUIT

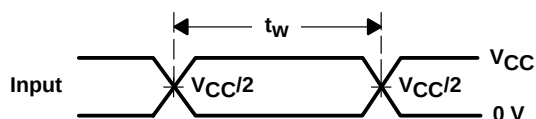
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



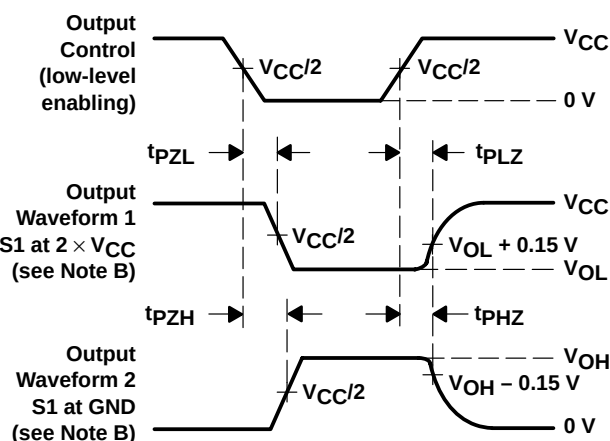
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



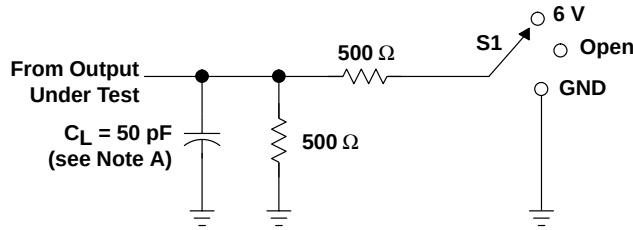
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

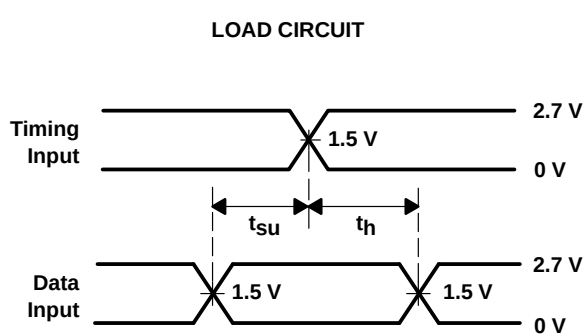
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

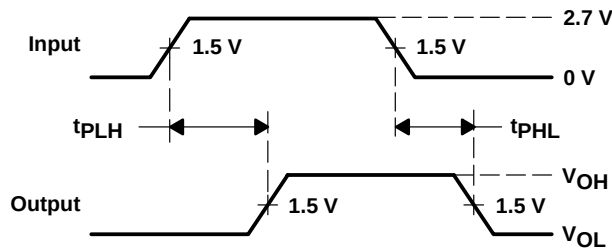


LOAD CIRCUIT

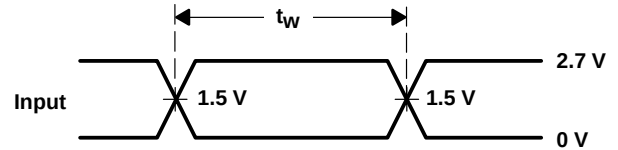
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



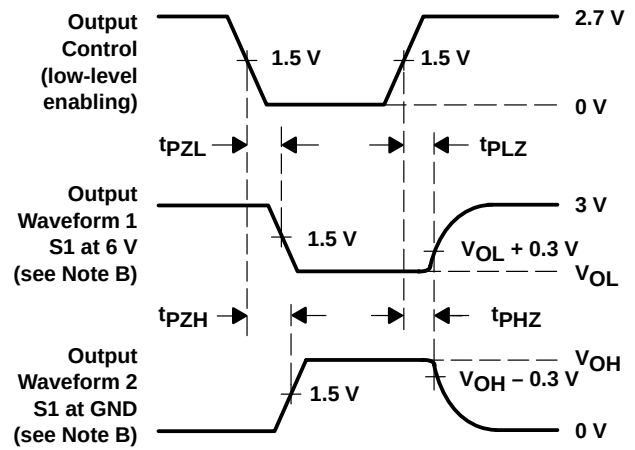
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES: A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
- D. The outputs are measured one at a time with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH162836

20-BIT UNIVERSAL BUS DRIVER WITH 3-STATE OUTPUTS

SCES122D – JULY 1997 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- Output Port Has Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- Designed to Comply With JEDEC 168-Pin and 200-Pin SDRAM Buffered DIMM Specification
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages

description

This 20-bit universal bus driver is designed for 1.65-V to 3.6-V V_{CC} operation.

Data flow from A to Y is controlled by the output-enable ($\overline{OE}$) input. The device operates in the transparent mode when the latch-enable ($\overline{LE}$) input is low. When $\overline{LE}$ is high, the A data is latched if the clock (CLK) input is held at a high or low logic level. If $\overline{LE}$ is high, the A data is stored in the latch/flip-flop on the low-to-high transition of CLK. When $\overline{OE}$ is high, the outputs are in the high-impedance state.

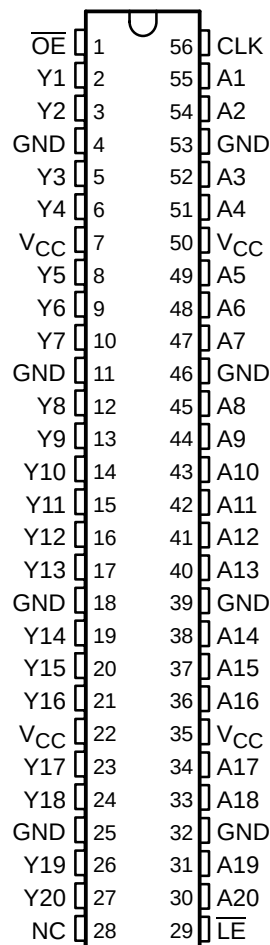
The output port includes equivalent 26-Ω series resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH162836 is characterized for operation from –40°C to 85°C.

DGG, DGV, OR DL PACKAGE (TOP VIEW)



NC – No internal connection

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SN74ALVCH162836
20-BIT UNIVERSAL BUS DRIVER
WITH 3-STATE OUTPUTS

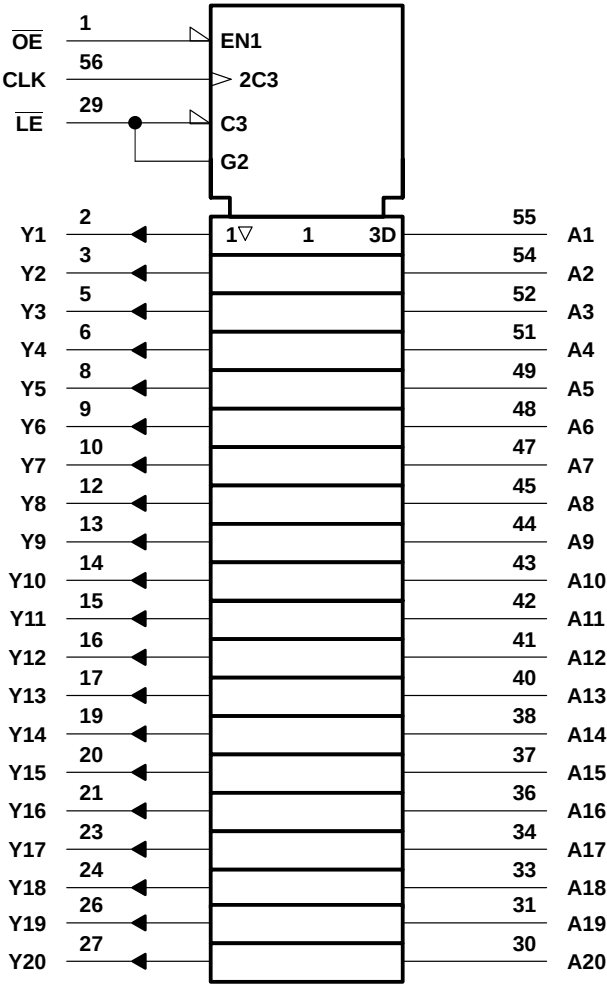
SCES122D – JULY 1997 – REVISED FEBRUARY 1999

FUNCTION TABLE

INPUTS				OUTPUT Y
OE	LE	CLK	A	
H	X	X	X	Z
L	L	X	L	L
L	L	X	H	H
L	H	↑	L	L
L	H	↑	H	H
L	H	L or H	X	Y ₀ [†]

† Output level before the indicated steady-state input conditions were established

logic symbol‡



‡ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Storage temperature range, T_{stg} -65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES:

1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

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20-BIT UNIVERSAL BUS DRIVER
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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–2	mA
		$V_{CC} = 2.3 \text{ V}$	–6	
		$V_{CC} = 2.7 \text{ V}$	–8	
		$V_{CC} = 3 \text{ V}$	–12	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	2	mA
		$V_{CC} = 2.3 \text{ V}$	6	
		$V_{CC} = 2.7 \text{ V}$	8	
		$V_{CC} = 3 \text{ V}$	12	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 µA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}		I _{OL} = 100 µA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V	±5			µA
I _I (hold)		V _I = 0.58 V	1.65 V	25			µA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			µA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			µA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	5.5			pF
	Data inputs			6			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	8			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.



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20-BIT UNIVERSAL BUS DRIVER WITH 3-STATE OUTPUTS

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

				V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
				MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency			†		150		150		150		MHz
t _w	Pulse duration	LE low		†		3.3		3.3		3.3		ns
		CLK high or low		†		3.3		3.3		3.3		
t _{su}	Setup time	Data before CLK↑		†		1.4		1.7		1.5		ns
		Data before LE↑	CLK high	†		1.2		1.6		1.3		
			CLK low	†		1.4		1.5		1.2		
t _h	Hold time	Data after CLK↑		†		0.9		0.9		0.9		ns
		Data after LE↑	CLK high or low	†		1.1		1.1		1.1		

† This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		150		150		150		MHz
t _{pd}	A	Y	†		1	4.4	4.6		1.2	4	ns
	$\overline{LE}$		†		1.1	5.8	6.1		1.4	5.1	
	CLK		†		1	5.2	5.5		1.1	5	
t _{en}	$\overline{OE}$	Y	†		1.1	6.4	6.5		1.2	5.5	ns
t _{dis}	$\overline{OE}$	Y	†		1	4.7	5.2		1.7	5.1	ns

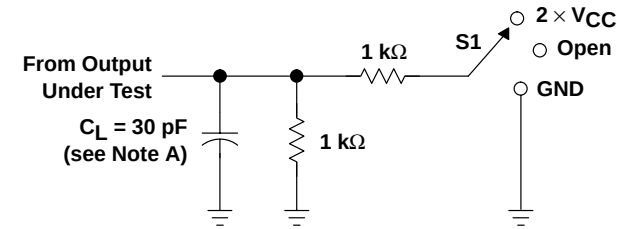
† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 0, f = 10 MHz	†	31.5	36	pF
		Outputs disabled		†	8	10.5	

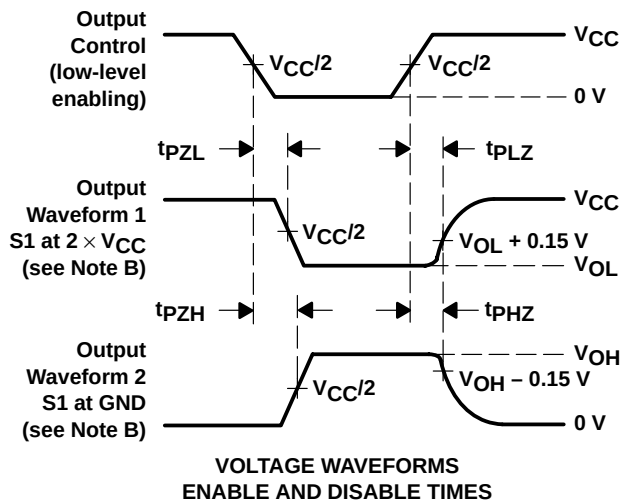
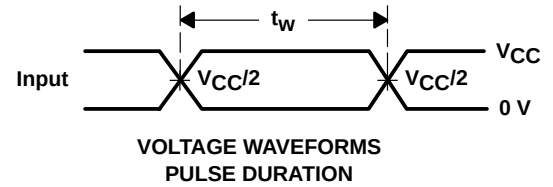
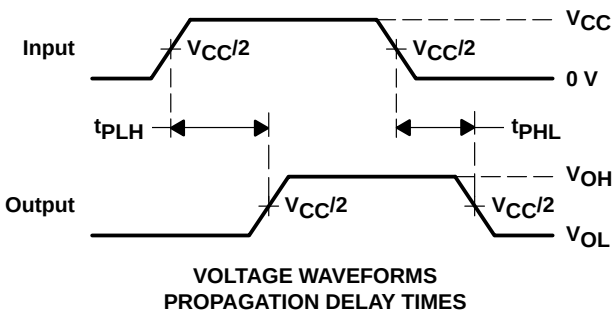
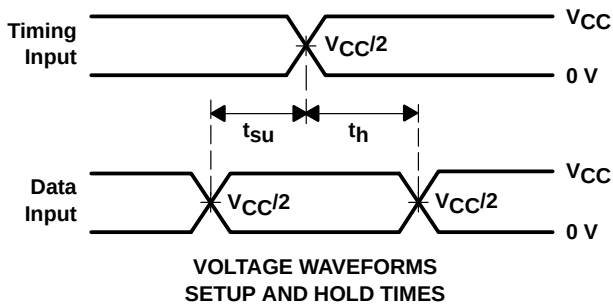
† This information was not available at the time of publication.

PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH162836

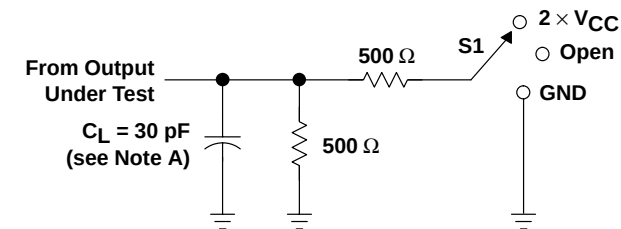
20-BIT UNIVERSAL BUS DRIVER

WITH 3-STATE OUTPUTS

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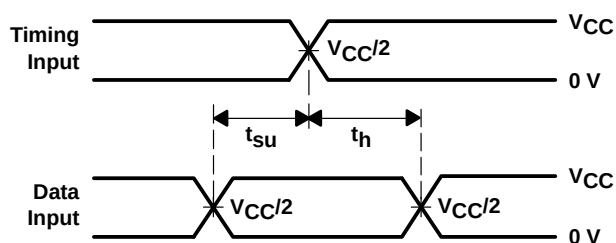
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

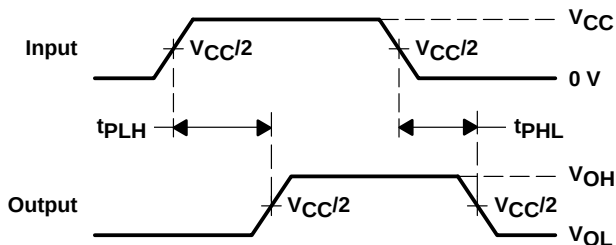


LOAD CIRCUIT

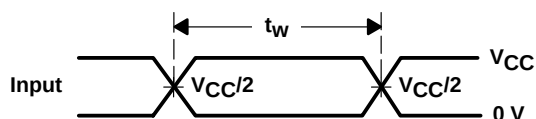
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



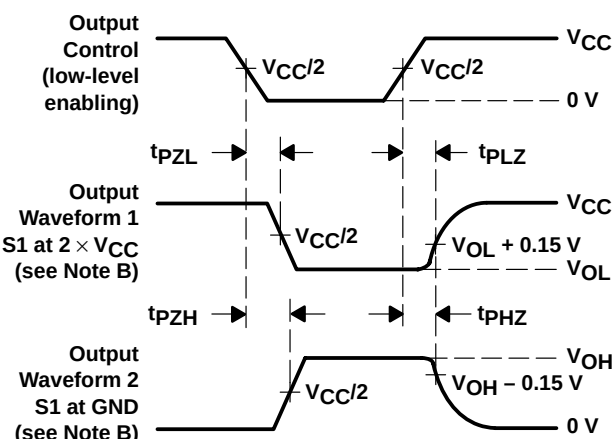
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



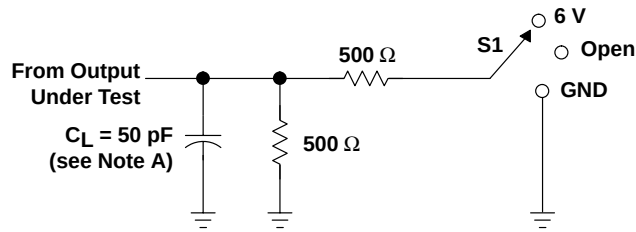
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

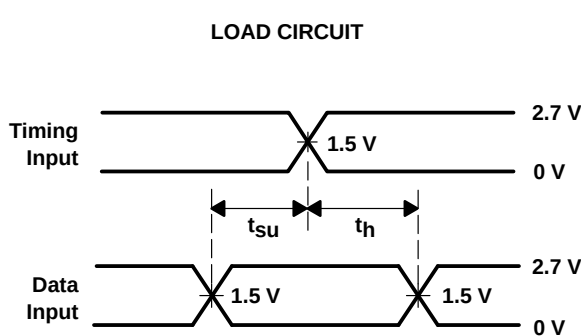
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

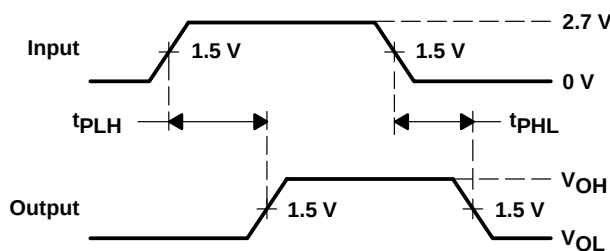


LOAD CIRCUIT

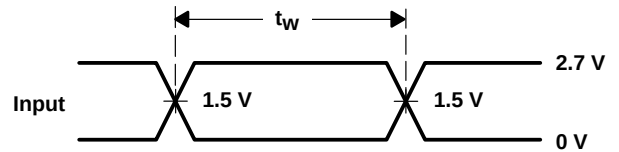
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



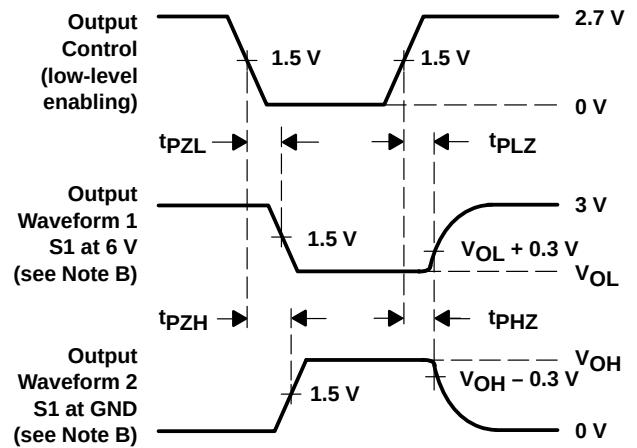
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALVCH162841

20-BIT BUS-INTERFACE D-TYPE LATCH WITH 3-STATE OUTPUTS

SCES088C – OCTOBER 1996 – REVISED FEBRUARY 1999

- Member of the Texas Instruments *Widebus*™ Family
- *EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Output Ports Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 20-bit bus-interface D-type latch is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH162841 features 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. This device is particularly suitable for implementing buffer registers, unidirectional bus drivers, and working registers.

The SN74ALVCH162841 can be used as two 10-bit latches or one 20-bit latch. The 20 latches are transparent D-type latches. The device has noninverting data (D) inputs and provides true data at its outputs. While the latch-enable (1LE or 2LE) input is high, the Q outputs of the corresponding 10-bit latch follow the D inputs. When LE is taken low, the Q outputs are latched at the levels set up at the D inputs.

A buffered output-enable ($\overline{1OE}$ or $\overline{2OE}$) input can be used to place the outputs of the corresponding 10-bit latch in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly.

$\overline{OE}$ does not affect the internal operation of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The outputs, which are designed to sink up to 12 mA, include equivalent 26-Ω resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

DGG OR DL PACKAGE
(TOP VIEW)

$\overline{1OE}$	1	56	1LE
1Q1	2	55	1D1
1Q2	3	54	1D2
GND	4	53	GND
1Q3	5	52	1D3
1Q4	6	51	1D4
V_{CC}	7	50	V_{CC}
1Q5	8	49	1D5
1Q6	9	48	1D6
1Q7	10	47	1D7
GND	11	46	GND
1Q8	12	45	1D8
1Q9	13	44	1D9
1Q10	14	43	1D10
2Q1	15	42	2D1
2Q2	16	41	2D2
2Q3	17	40	2D3
GND	18	39	GND
2Q4	19	38	2D4
2Q5	20	37	2D5
2Q6	21	36	2D6
V_{CC}	22	35	V_{CC}
2Q7	23	34	2D7
2Q8	24	33	2D8
GND	25	32	GND
2Q9	26	31	2D9
2Q10	27	30	2D10
$\overline{2OE}$	28	29	2LE

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SN74ALVCH162841
20-BIT BUS-INTERFACE D-TYPE LATCH
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description (continued)

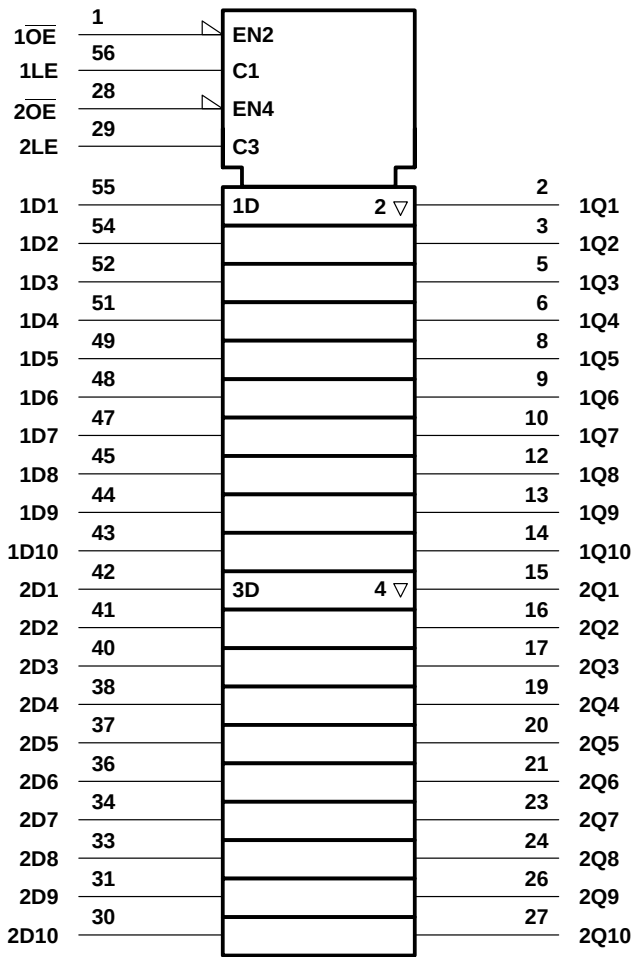
Active bus-hold circuitry is provided to hold unused or floating inputs at a valid logic level.

The SN74ALVCH162841 is characterized for operation from –40°C to 85°C.

FUNCTION TABLE
(each 10-bit latch)

INPUTS			OUTPUT Q
OE	LE	D	
L	H	H	H
L	H	L	L
L	L	X	Q ₀
H	X	X	Z

logic symbol†

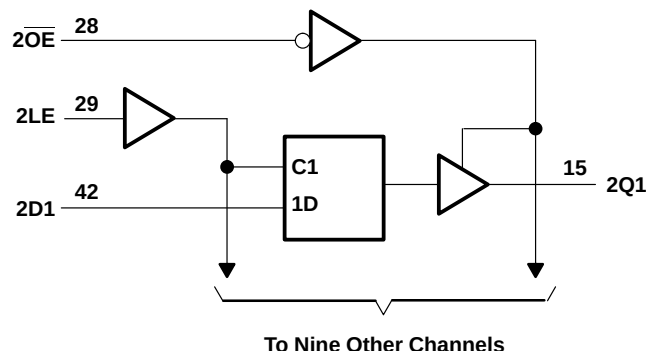
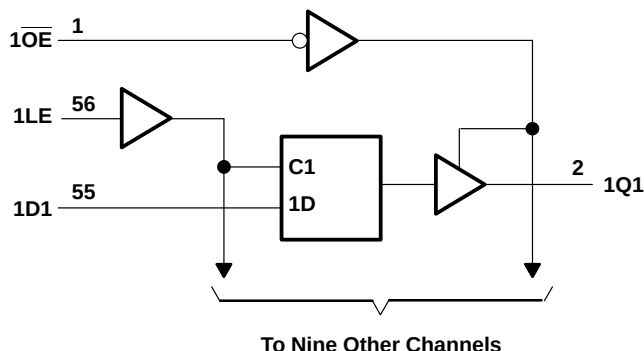


† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

SN74ALVCH162841
20-BIT BUS-INTERFACE D-TYPE LATCH
WITH 3-STATE OUTPUTS

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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T_{Stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

SN74ALVCH162841
20-BIT BUS-INTERFACE D-TYPE LATCH
WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65\text{ V to }1.95\text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3\text{ V to }2.7\text{ V}$	1.7	
		$V_{CC} = 2.7\text{ V to }3.6\text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65\text{ V to }1.95\text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3\text{ V to }2.7\text{ V}$	0.7	
		$V_{CC} = 2.7\text{ V to }3.6\text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65\text{ V}$	–2	mA
		$V_{CC} = 2.3\text{ V}$	–6	
		$V_{CC} = 2.7\text{ V}$	–8	
		$V_{CC} = 3\text{ V}$	–12	
I_{OL}	Low-level output current	$V_{CC} = 1.65\text{ V}$	2	mA
		$V_{CC} = 2.3\text{ V}$	6	
		$V_{CC} = 2.7\text{ V}$	8	
		$V_{CC} = 3\text{ V}$	12	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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20-BIT BUS-INTERFACE D-TYPE LATCH
WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 μA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}		I _{OL} = 100 μA	1.65 V to 3.6 V			0.2	V
		I _{OL} = 2 mA	1.65 V			0.45	
		I _{OL} = 4 mA	2.3 V			0.4	
		I _{OL} = 6 mA	2.3 V			0.55	
			3 V			0.55	
		I _{OL} = 8 mA	2.7 V			0.6	
		I _{OL} = 12 mA	3 V			0.8	
I _I		V _I = V _{CC} or GND	3.6 V			±5	μA
I _I (hold)		V _I = 0.58 V	1.65 V	25			μA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V			±500	
I _{OZ}		V _O = V _{CC} or GND	3.6 V			±10	μA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V			40	μA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V			750	μA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	4.5			pF
	Data inputs			6.5			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER		V _{CC} = 1.8 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t _w	Pulse duration, LE high or low	§		3.3		3.3		3.3		ns
t _{su}	Setup time, data before LE↑	§		0.9		0.7		1.1		ns
t _h	Hold time, data after LE↑	§		1.2		1.5		1.1		ns

§ This information was not available at the time of publication.



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20-BIT BUS-INTERFACE D-TYPE LATCH
WITH 3-STATE OUTPUTS

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	D	Q	†	1	5.3	5.2		1.2	4.3	ns
	LE		†	1	5.9	5.6		1	4.7	
t _{en}	$\overline{OE}$	Q	†	1	6.5	6.5		1	5.3	ns
t _{dis}	$\overline{OE}$	Q	†	1.1	5.6	4.9		1.3	4.4	ns

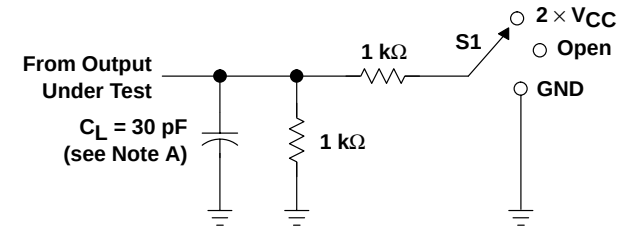
† This information was not available at the time of publication.

operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance	Outputs enabled	C _L = 0, f = 10 MHz	†	24	27	pF
		Outputs disabled		†	2	2	

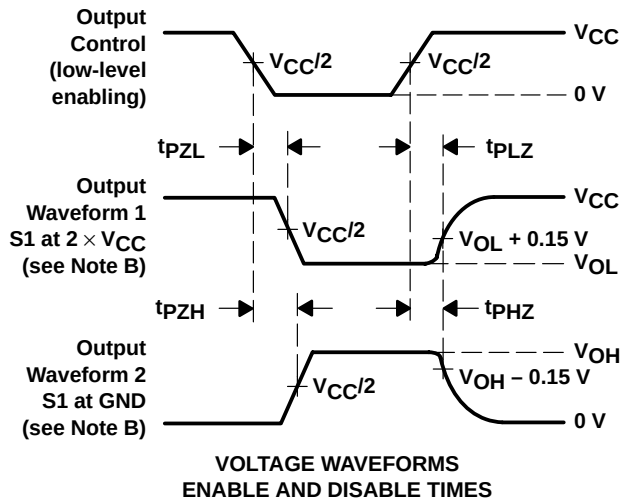
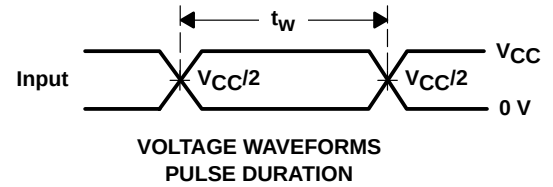
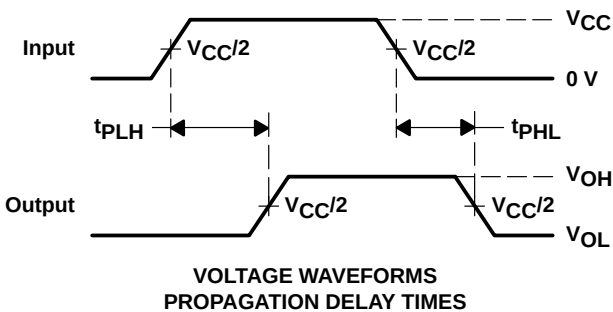
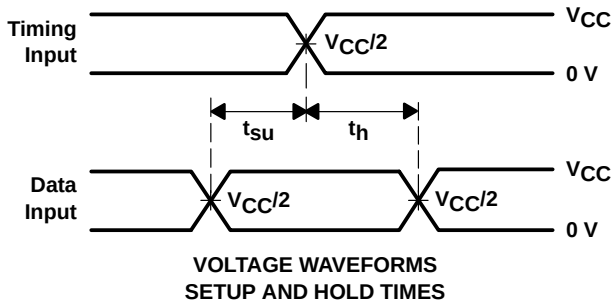
† This information was not available at the time of publication.

PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 1.8\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH162841

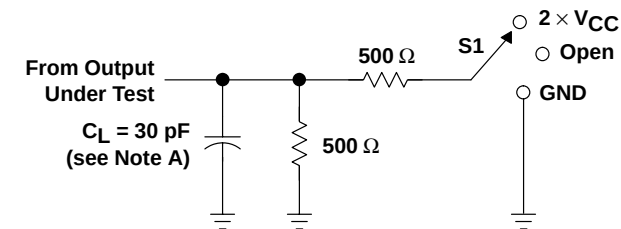
20-BIT BUS-INTERFACE D-TYPE LATCH

WITH 3-STATE OUTPUTS

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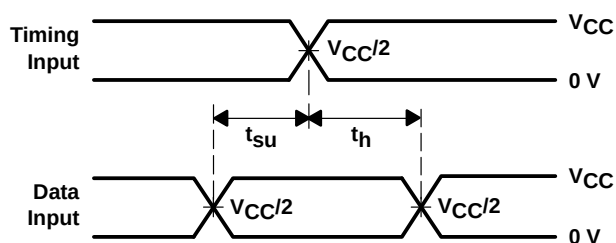
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

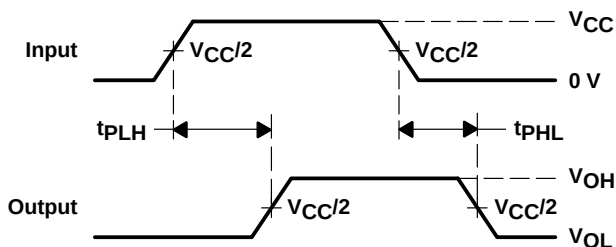


LOAD CIRCUIT

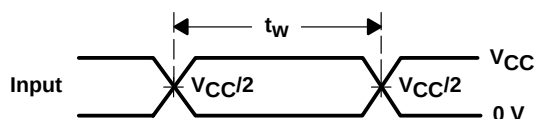
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



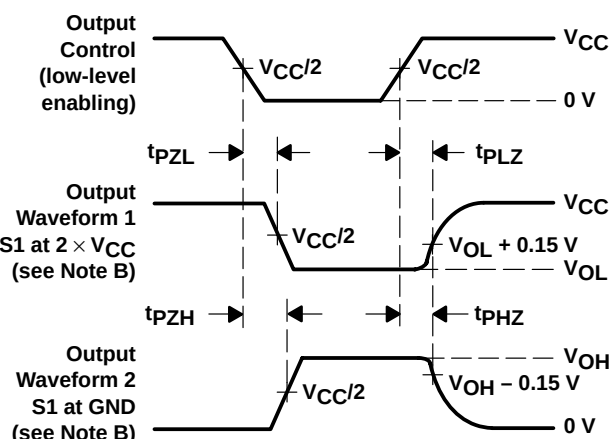
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



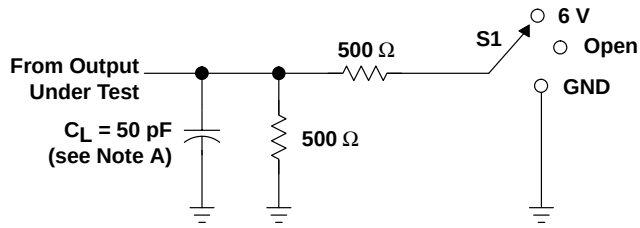
VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

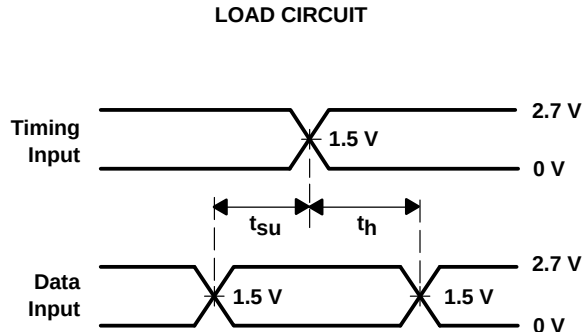
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

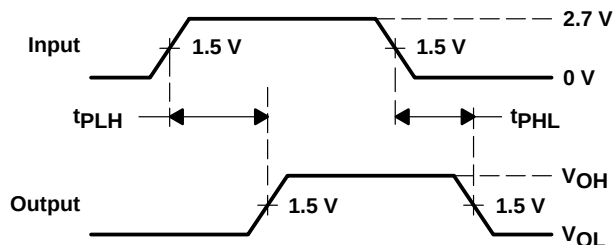


LOAD CIRCUIT

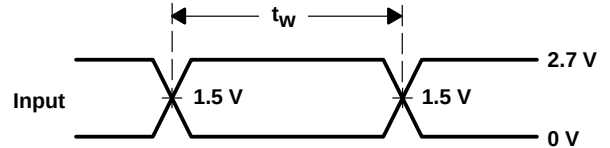
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



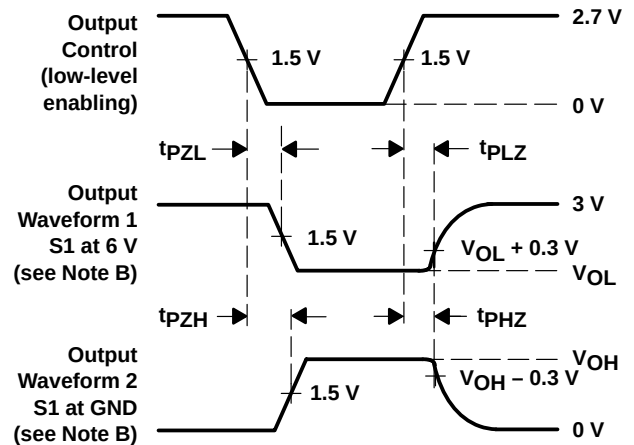
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

General Information	1
ALVC Gates/Octals	2
ALVC Widebus™/Widebus+™	3
ALVC Widebus™ With Series Damping Resistors	4
ALVC Dual-Supply-Voltage Translators	5
SSTL	6
HSTL	7
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SN74ALVC164245

16-BIT 3.3-V TO 5-V LEVEL SHIFTING TRANSCEIVER WITH 3-STATE OUTPUTS

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- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

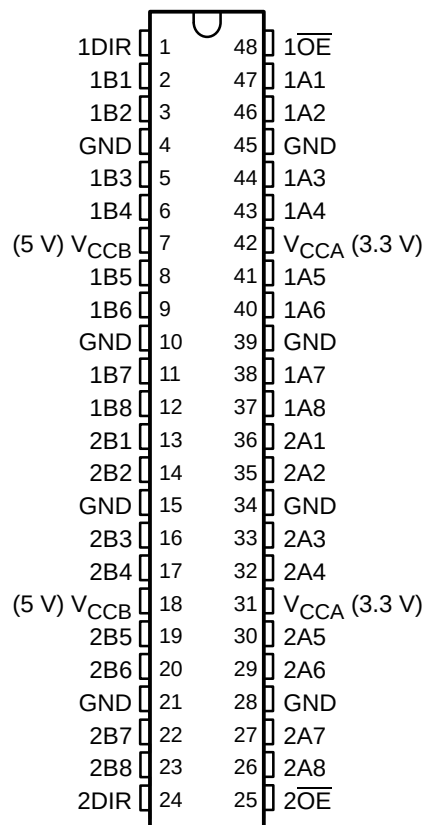
This 16-bit (dual-octal) noninverting bus transceiver contains two separate supply rails; B port has V_{CCB} , which is set at 5 V, and A port has V_{CCA} , which is set to operate at 3.3 V. This allows for translation from a 3.3-V to a 5-V environment and vice versa.

The SN74ALVC164245 is designed for asynchronous communication between data buses.

To ensure the high-impedance state during power up or power down, the output-enable ($\overline{OE}$) input should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74ALVC164245 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)



FUNCTION TABLE
(each 8-bit section)

INPUTS		OPERATION
$\overline{OE}$	DIR	
L	L	B data to A bus
L	H	A data to B bus
H	X	Isolation

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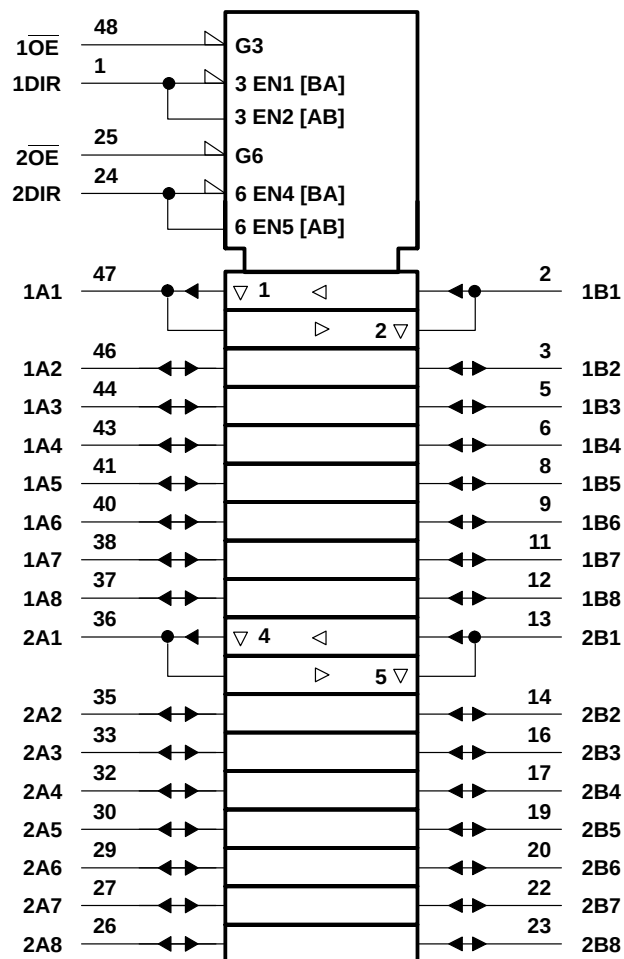
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SN74ALVC164245

16-BIT 3.3-V TO 5-V LEVEL SHIFTING TRANSCEIVER WITH 3-STATE OUTPUTS

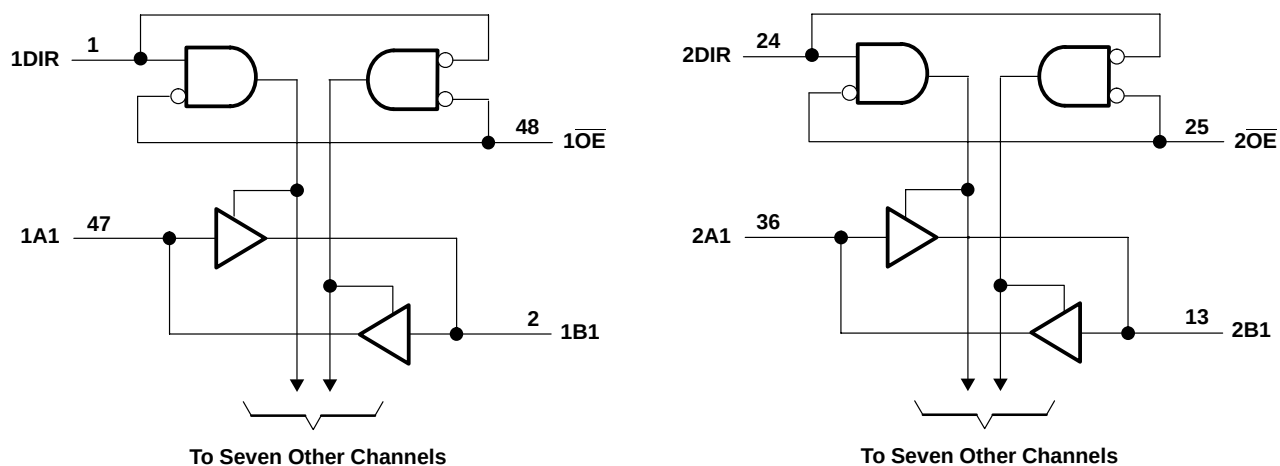
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logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



SN74ALVC164245
16-BIT 3.3-V TO 5-V LEVEL SHIFTING TRANSCEIVER
WITH 3-STATE OUTPUTS

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absolute maximum ratings over operating free-air temperature range for V_{CCB} at 5 V and V_{CCA} at 3.3 V (unless otherwise noted)[†]

Supply voltage range: V_{CCA}	–0.5 V to 4.6 V
V_{CCB}	–0.5 V to 6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 6 V
I/O port A (see Note 2)	–0.5 V to $V_{CCA} + 0.5$ V
I/O port B (see Note 1)	–0.5 V to $V_{CCB} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	89°C/W
DL package	94°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. This value is limited to 6 V maximum.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions for V_{CCB} at 5 V (see Note 4)

	MIN	MAX	UNIT
V_{CCB} Supply voltage	4.5	5.5	V
V_{IH} High-level input voltage	2		V
V_{IL} Low-level input voltage		0.8	V
V_{IA} Input voltage	0	V_{CCB}	V
V_{OB} Output voltage	0	V_{CCB}	V
I_{OH} High-level output current		–24	mA
I_{OL} Low-level output current		24	mA
$\Delta t/\Delta v$ Input transition rise or fall rate		10	ns/V
T_A Operating free-air temperature	–40	85	°C

NOTE 4: All unused inputs of the device must be held at the associated V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



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16-BIT 3.3-V TO 5-V LEVEL SHIFTING TRANSCEIVER

WITH 3-STATE OUTPUTS

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recommended operating conditions for V_{CCA} at 3.3 V (see Note 4)

		MIN	MAX	UNIT
V_{CCA}	Supply voltage	2.7	3.6	V
V_{IH}	High-level input voltage	$V_{CCA} = 2.7 \text{ V to } 3.6 \text{ V}$		V
V_{IL}	Low-level input voltage	$V_{CCA} = 2.7 \text{ V to } 3.6 \text{ V}$		V
V_{IB}	Input voltage	0	V_{CCA}	V
V_{OA}	Output voltage	0	V_{CCA}	V
I_{OH}	High-level output current	$V_{CCA} = 2.7 \text{ V}$	-12	mA
		$V_{CCA} = 3 \text{ V}$	-24	
I_{OL}	Low-level output current	$V_{CCA} = 2.7 \text{ V}$	12	mA
		$V_{CCA} = 3 \text{ V}$	24	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	-40	85	°C

NOTE 4: All unused inputs of the device must be held at the associated V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range for $V_{CCB} = 5 \text{ V}$ (unless otherwise noted) (see Note 5)

PARAMETER	TEST CONDITIONS	V_{CCB}	MIN	TYP [†]	MAX	UNIT
V_{OH} (A to B)	$I_{OH} = -100 \mu\text{A}$	4.5 V	4.3			V
		5.5 V	5.3			
	$I_{OH} = -24 \text{ mA}$	4.5 V	3.7			
		5.5 V	4.7			
V_{OL} (A to B)	$I_{OL} = 100 \mu\text{A}$	4.5 V			0.2	V
		5.5 V			0.2	
	$I_{OL} = 24 \text{ mA}$	4.5 V			0.55	
		5.5 V			0.55	
I_I	Control inputs	$V_I = V_{CCB}$ or GND	5.5 V		± 5	μA
$I_{OZ}^{\ddagger}$	A or B ports	$V_O = V_{CCB}$ or GND	5.5 V		± 10	μA
I_{CC}		$V_I = V_{CCB}$ or GND, $I_O = 0$	5.5 V		40	μA
$\Delta I_{CC}^{\S}$		One input at 3.4 V, Other inputs at V_{CCB} or GND	4.5 V to 5.5 V		750	μA
C_i	Control inputs	$V_I = V_{CCB}$ or GND	5 V		6.5	pF
C_{i0}	A or B ports	$V_O = V_{CCB}$ or GND	5 V		6.5	pF

[†] Typical values are measured at $V_{CC} = 3.3 \text{ V}$, $T_A = 25^\circ\text{C}$.

[‡] For I/O ports, the parameter I_{OZ} includes the input leakage current.

[§] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than at 0 or the associated V_{CC} .

NOTE 5: $V_{CCA} = 2.7 \text{ V to } 3.6 \text{ V}$



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16-BIT 3.3-V TO 5-V LEVEL SHIFTING TRANSCEIVER
WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range for $V_{CCA} = 3.3\text{ V}$ (unless otherwise noted) (see Note 6)

PARAMETER		TEST CONDITIONS	V_{CCA}	MIN	TYP [†]	MAX	UNIT
V_{OH} (B to A)		$I_{OH} = -100\text{ }\mu\text{A}$	2.7 V to 3.6 V	$V_{CC}-0.2$			V
		$I_{OH} = -12\text{ mA}$	2.7 V	2.2			
			3 V	2.4			
		$I_{OH} = -24\text{ mA}$	3 V	2			
V_{OL} (B to A)		$I_{OL} = 100\text{ }\mu\text{A}$	2.7 V to 3.6 V	0.2			V
		$I_{OL} = 12\text{ mA}$	2.7 V	0.4			
		$I_{OL} = 24\text{ mA}$	3 V	0.55			
I_I	Control inputs	$V_I = V_{CCA}$ or GND	3.6 V	± 5			μA
$I_{OZ}^{\ddagger}$		$V_O = V_{CCA}$ or GND	3.6 V	± 10			μA
I_{CC}		$V_I = V_{CCA}$ or GND, $I_O = 0$	3.6 V	40			μA
$\Delta I_{CC}^{\S}$		One input at $V_{CCA} - 0.6\text{ V}$, Other inputs at V_{CCA} or GND	3 V to 3.6 V	750			μA
C_i	Control inputs	$V_I = V_{CCA}$ or GND	3.3 V	6.5			pF
C_{iO}	A or B ports	$V_O = V_{CCA}$ or GND	3.3 V	8.5			pF

[†] Typical values are measured at $V_{CC} = 3.3\text{ V}$, $T_A = 25^\circ\text{C}$.

[‡] For I/O ports, the parameter I_{OZ} includes the input leakage current.

[§] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than at 0 or the associated V_{CC} .

NOTE 6: $V_{CCB} = 5\text{ V} \pm 0.5\text{ V}$

switching characteristics over recommended operating free-air temperature range, $C_L = 50\text{ pF}$ (unless otherwise noted) (see Figures 1 and 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CCB} = 5 V ± 0.5 V				UNIT
			V _{CCA} = 2.7 V		V _{CCA} = 3.3 V ± 0.3 V		
			MIN	MAX [†]	MIN [†]	MAX [†]	
t _{pd}	A	B	5.9		1	5.8	ns
	B	A	6.7		1.2	5.8	
t _{en}	$\overline{OE}$	B	9.3		1	8.9	ns
t _{dis}	$\overline{OE}$	B	9.2		2.1	9.5	ns
t _{en}	$\overline{OE}$	A	10.2		2	9.1	ns
t _{dis}	$\overline{OE}$	A	9		2.9	8.6	ns

[¶] This limit can vary among suppliers.

operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER			TEST CONDITIONS	$V_{CCA} = 3.3\text{ V}$ $V_{CCB} = 5\text{ V}$	UNIT
				TYP	
C_{pd}	Power dissipation capacitance	Outputs enabled (A or B)	$C_L = 50\text{ pF}$, $f = 10\text{ MHz}$	56	pF
		Outputs disabled (A or B)		6	

SN74ALVC164245

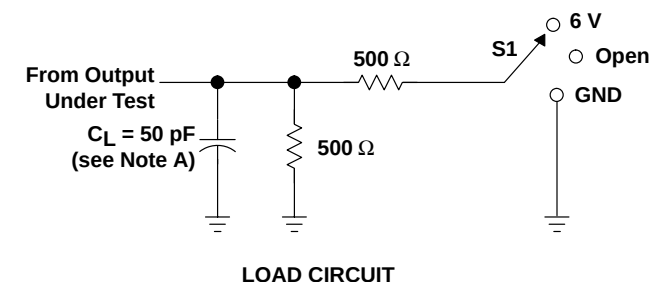
16-BIT 3.3-V TO 5-V LEVEL SHIFTING TRANSCEIVER

WITH 3-STATE OUTPUTS

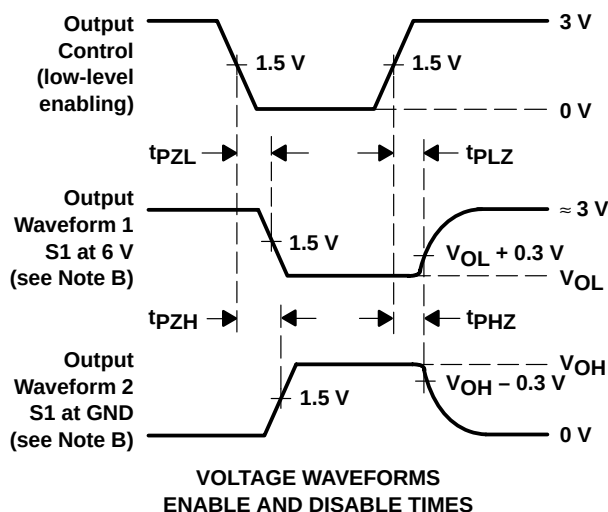
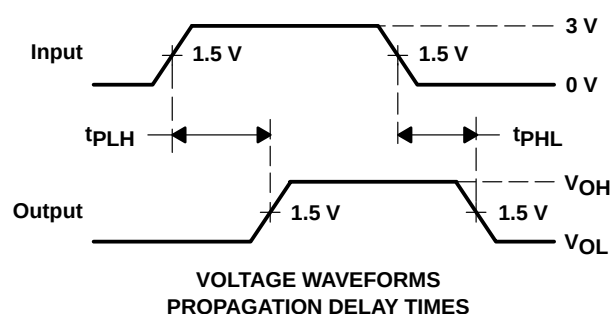
SCAS416F – MARCH 1994 – REVISED FEBRUARY 1999

PARAMETER MEASUREMENT INFORMATION

$V_{CCA} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$



TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

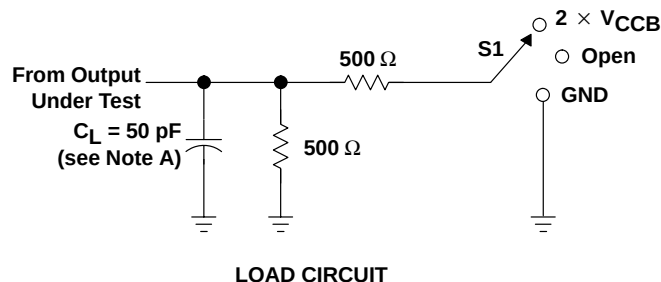
SN74ALVC164245

16-BIT 3.3-V TO 5-V LEVEL SHIFTING TRANSCIEVER WITH 3-STATE OUTPUTS

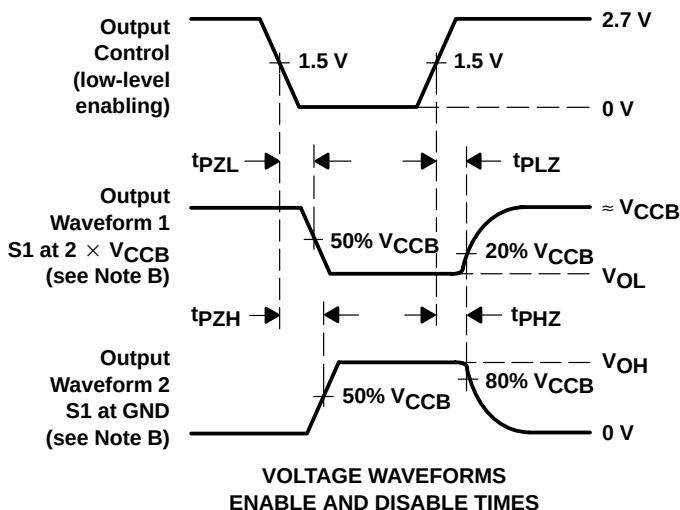
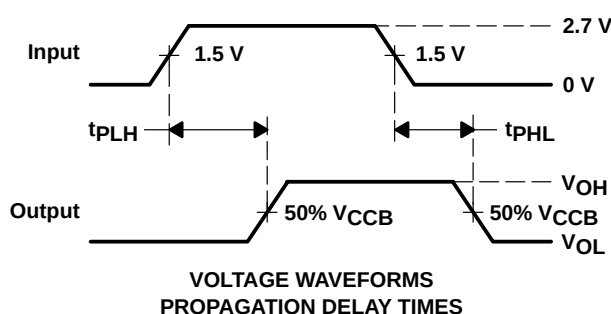
SCAS416F – MARCH 1994 – REVISED FEBRUARY 1999

PARAMETER MEASUREMENT INFORMATION

$$V_{CCB} = 5\text{ V} \pm 0.5\text{ V}$$



TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CCB}$
t_{PHZ}/t_{PZH}	GND



- OTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{djs} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

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SN74SSTL16837A

20-BIT SSTL_3 INTERFACE UNIVERSAL BUS DRIVER WITH 3-STATE OUTPUTS

SCBS675G – SEPTEMBER 1996 – REVISED SEPTEMBER 1998

- Member of the Texas Instruments *Widebus™* Family
- Supports SSTL_3 Signal Inputs and Outputs
- Flow-Through Architecture Optimizes PCB Layout
- Meets SSTL_3 Class I and Class II Specifications
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Packaged in Plastic Thin Shrink Small-Outline Package

description

This 20-bit universal bus driver is designed for 3-V to 3.6-V V_{CC} operation and SSTL_3 or LVTTTL I/O levels.

Data flow from A to Y is controlled by the output-enable ($\overline{OE}$) input. The device operates in the transparent mode when latch enable (LE) is high. The A data is latched if LE is low and clock (CLK) is held at a high or low logic level. If LE is low, the A data is stored in the latch/flip-flop on the low-to-high transition of CLK. When $\overline{OE}$ is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74SSTL16837A is characterized for operation from 0°C to 70°C.

DGG PACKAGE
(TOP VIEW)

Y1	1	64	A1
Y2	2	63	A2
GND	3	62	GND
Y3	4	61	A3
Y4	5	60	A4
V_{DDQ}	6	59	V_{CC}
Y5	7	58	A5
Y6	8	57	A6
GND	9	56	GND
Y7	10	55	A7
Y8	11	54	A8
V_{DDQ}	12	53	V_{CC}
Y9	13	52	A9
Y10	14	51	A10
GND	15	50	GND
$\overline{OE}$	16	49	CLK
V_{REF}	17	48	LE
GND	18	47	GND
Y11	19	46	A11
Y12	20	45	A12
V_{DDQ}	21	44	V_{CC}
Y13	22	43	A13
Y14	23	42	A14
GND	24	41	GND
Y15	25	40	A15
Y16	26	39	A16
V_{DDQ}	27	38	V_{CC}
Y17	28	37	A17
Y18	29	36	A18
GND	30	35	GND
Y19	31	34	A19
Y20	32	33	A20

Widebus is a trademark of Texas Instruments Incorporated.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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SN74SSTL16837A

20-BIT SSTL_3 INTERFACE UNIVERSAL BUS DRIVER

WITH 3-STATE OUTPUTS

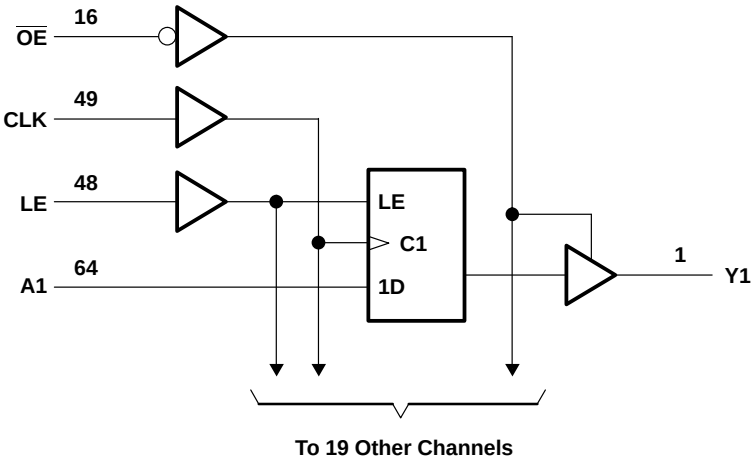
SCBS675G – SEPTEMBER 1996 – REVISED SEPTEMBER 1998

FUNCTION TABLE				
INPUTS				OUTPUT Y
OE	LE	CLK	A	
L	H	X	H	H
L	H	X	L	L
L	L	↑	H	H
L	L	↑	L	L
L	L	H	X	Y ₀ [†]
L	L	L	X	Y ₀ [‡]
H	X	X	X	Z

[†] Output level before the indicated steady-state input conditions were established, provided that CLK was high before LE went low

[‡] Output level before the indicated steady-state input conditions were established

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[§]

Supply voltage range, V _{CC} or V _{DDQ}	–0.5 V to 4.6 V
Input voltage range, V _I (see Note 1)	–0.5 V to V _{CC} + 0.5 V
Output voltage range, V _O (see Notes 1 and 2)	–0.5 V to V _{DDQ} + 0.5 V
Input clamp current, I _{IK} (V _I < 0)	–50 mA
Output clamp current, I _{OK} (V _O < 0)	–50 mA
Continuous output current, I _O (V _O = 0 to V _{DDQ})	±50 mA
Continuous current through each V _{CC} , V _{DDQ} , or GND	±100 mA
Package thermal impedance, θ _{JA} (see Note 3)	73°C/W
Storage temperature range, T _{stg}	–65°C to 150°C

[§] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:

 - The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
 - This current flows only when the output is in the high state and V_O > V_{DDQ}.
 - The package thermal impedance is calculated in accordance with JESD 51.

SN74SSTL16837A

20-BIT SSTL_3 INTERFACE UNIVERSAL BUS DRIVER WITH 3-STATE OUTPUTS

SCBS675G – SEPTEMBER 1996 – REVISED SEPTEMBER 1998

recommended operating conditions (see Note 4)

		MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage	V _{DDQ}		3.6	V
V _{DDQ}	Output supply voltage	3		3.6	V
V _{REF}	Reference voltage (V _{REF} = 0.45 × V _{DDQ})	1.3	1.5	1.7	V
V _{TT}	Termination voltage (V _{REF} = V _{TT} = 0.45 × V _{DDQ})	V _{REF} –50mV	V _{REF}	V _{REF} +50mV	V
V _I	Input voltage	0		V _{CC}	V
V _{IH}	AC high-level input voltage	All inputs		V _{REF} +400mV	V
V _{IL}	AC low-level input voltage	All inputs		V _{REF} –400mV	V
V _{IH}	DC high-level input voltage	All inputs		V _{REF} +200mV	V
V _{IL}	DC low-level input voltage	All inputs		V _{REF} –200mV	V
I _{OH}	High-level output current			–20	mA
I _{OL}	Low-level output current			20	
T _A	Operating free-air temperature	0		70	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{IK}		I _I = −18 mA		3 V			−1.2	V
V _{OH}		I _{OH} = −100 μA		3 V to 3.6 V	V _{CC} −0.2			V
		I _{OH} = −16 mA		3 V	2.2			
		I _{OH} = −20 mA			2.1			
V _{OL}		I _{OL} = 100 μA		3 V to 3.6 V	0.2		V	
		I _{OL} = 16 mA		3 V	0.5			
		I _{OL} = 20 mA			0.55			
I _I	LE	V _I = 2.1 V or 0.9 V	V _{REF} = 1.3 V or 1.7 V	3.6 V	±40		μA	
		V _I = 3.6 V or 0			±1.2		mA	
	Data inputs, $\overline{OE}$	V _I = 2.1 V or 0.9 V	V _{REF} = 1.3 V or 1.7 V	3.6 V	±5		μA	
		V _I = 3.6 V or 0			±5			
	CLK	V _I = 2.1 V or 0.9 V	V _{REF} = 1.3 V or 1.7 V	3.6 V	±150		mA	
		V _I = 3.6 V or 0			±4			
	V _{REF}	V _{REF} = 1.3 V or 1.7 V			3.6 V	±150		μA
I _{OZ}		V _O = 0.9 V or 2.1 V		3.6 V	±10		μA	
		V _O = 0 or 3.6 V			±10			
I _{CC}		V _I = 2.1 V or 0.9 V	I _O = 0	3.6 V	90		mA	
		V _I = 3.6 V or 0			90			
C _i	Control inputs	V _I = 2.1 V or 0.9 V		3.3 V	2.5		pF	
	A port				2			
C _O	Y port	V _O = 2.1 V or 0.9 V		3.3 V	3		pF	

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.



SN74SSTL16837A

20-BIT SSTL_3 INTERFACE UNIVERSAL BUS DRIVER

WITH 3-STATE OUTPUTS

SCBS675G – SEPTEMBER 1996 – REVISED SEPTEMBER 1998

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

			$V_{CC} = 3.3\text{ V}$ $\pm 0.3\text{ V}$		UNIT
			MIN	MAX	
f_{clock}	Clock frequency		200		MHz
t_w	Pulse duration	LE high	2.5		ns
		CLK high or low	2.5		
t_{su}	Setup time	A before CLK $\uparrow$	LE low	1.5	ns
		A before LE $\downarrow$	CLK high	1.5	
			CLK low	2	
t_h	Hold time	A after CLK $\uparrow$	LE low	1	ns
		A after LE $\downarrow$		1	

switching characteristics over recommended operating free-air temperature range,
Class I, $V_{\text{REF}} = V_{\text{TT}} = V_{\text{DDQ}} \times 0.45$ and $C_L = 10\text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 3.3\text{ V}$ $\pm 0.3\text{ V}$		UNIT
			MIN	MAX	
f_{max}			200		MHz
t_{pd}	A	Y	1.1	4	ns
	LE		1.5	4.1	
	CLK		1	3	
t_{en}	$\overline{\text{OE}}$	Y	1.8	5.5	ns
t_{dis}	$\overline{\text{OE}}$	Y	1.8	6	ns

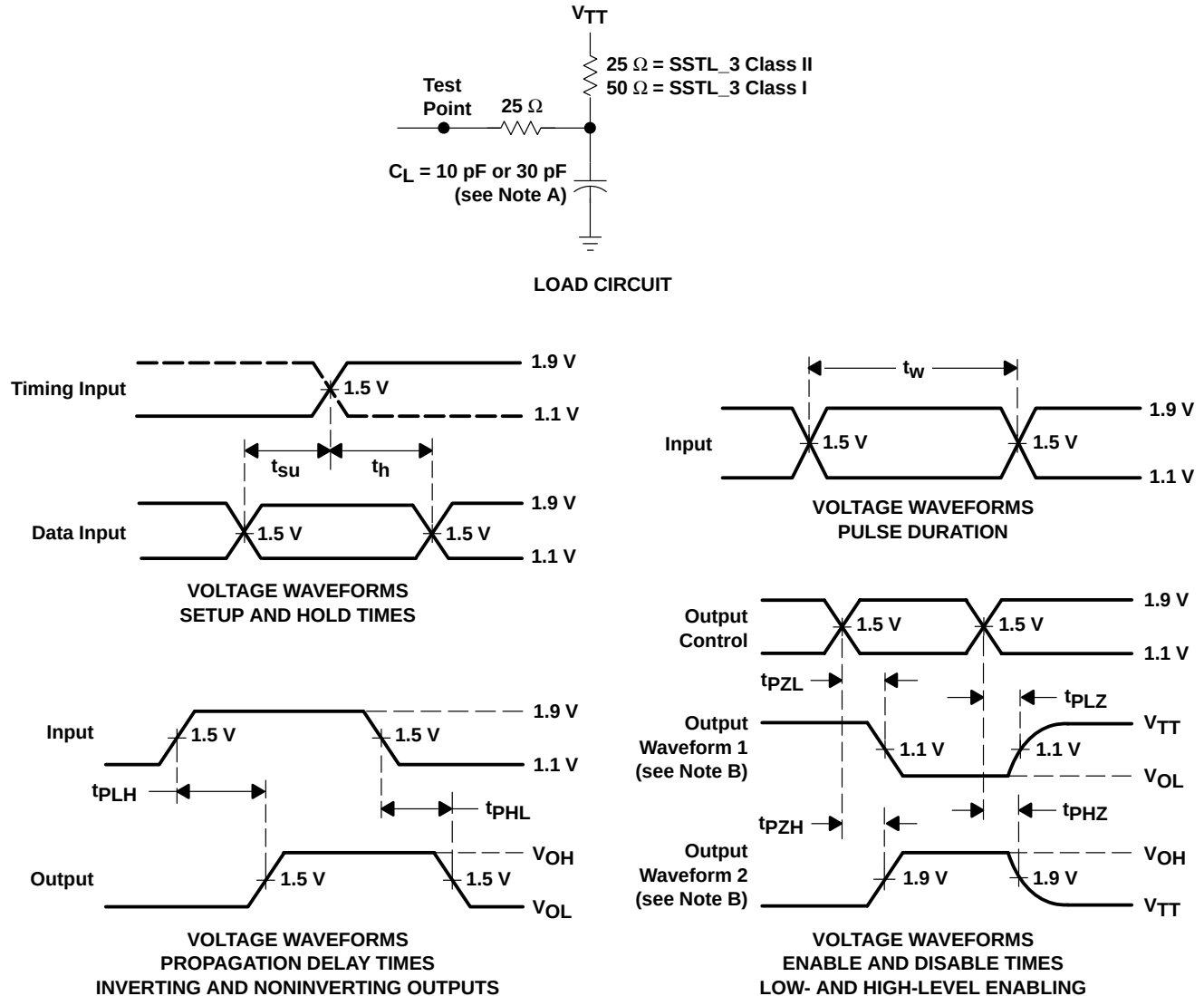
switching characteristics over recommended operating free-air temperature range,
Class II, $V_{\text{REF}} = V_{\text{TT}} = V_{\text{DDQ}} \times 0.45$ and $C_L = 30\text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 3.3\text{ V}$ $\pm 0.3\text{ V}$		UNIT
			MIN	MAX	
f_{max}			200		MHz
t_{pd}	A	Y	1.1	4.2	ns
	LE		1.5	4.3	
	CLK		1	3.2	
t_{en}	$\overline{\text{OE}}$	Y	1.8	5.5	ns
t_{dis}	$\overline{\text{OE}}$	Y	1.8	6	ns

SN74SSTL16837A 20-BIT SSTL_3 INTERFACE UNIVERSAL BUS DRIVER WITH 3-STATE OUTPUTS

SCBS675G – SEPTEMBER 1996 – REVISED SEPTEMBER 1998

PARAMETER MEASUREMENT INFORMATION



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\ \text{MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 1\ \text{ns}$, $t_f \leq 1\ \text{ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - $V_{TT} = V_{REF} = V_{CC} \times 0.45$
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PHL} and t_{PLH} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74SSTL16847

20-BIT SSTL_3 INTERFACE BUFFER WITH 3-STATE OUTPUTS

SCBS709A – OCTOBER 1997 – REVISED MAY 1998

- Member of the Texas Instruments Widebus™ Family
- Supports SSTL_3 Signal Inputs and Outputs
- Flow-Through Architecture Optimizes PCB Layout
- Meets SSTL_3 Class I and Class II Specifications
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Packaged in Plastic Thin Shrink Small-Outline Package

description

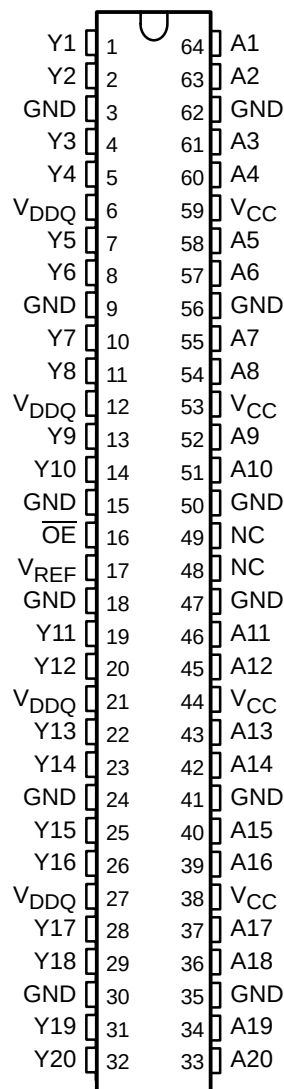
This 20-bit buffer is designed for 3-V to 3.6-V V_{CC} operation and SSTL_3 input levels.

Data flow from A to Y is controlled by the output-enable ($\overline{OE}$). When $\overline{OE}$ is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74SSTL16847 is characterized for operation from 0°C to 70°C.

DGG PACKAGE (TOP VIEW)



NC – No internal connection

Widebus is a trademark of Texas Instruments Incorporated.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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SN74SSTL16847

20-BIT SSTL_3 INTERFACE BUFFER

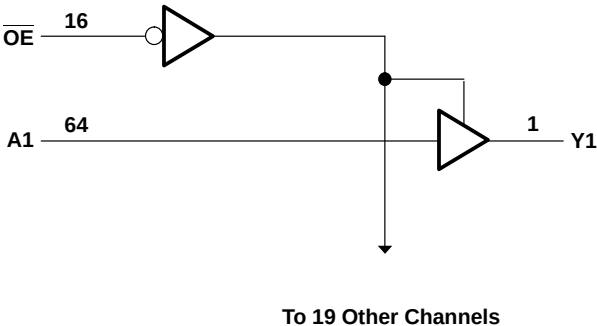
WITH 3-STATE OUTPUTS

SCBS709A – OCTOBER 1997 – REVISED MAY 1998

FUNCTION TABLE

INPUTS		OUTPUT
OE	A	Y
L	H	H
L	L	L
H	X	Z

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC} or V_{DDQ}	−0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	−0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	−0.5 V to $V_{DDQ} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	−50 mA
Output clamp current, I_{OK} ($V_O < 0$)	−50 mA
Continuous output current, I_O ($V_O = 0$ to V_{DDQ})	±50 mA
Continuous current through each V_{CC} , V_{DDQ} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3):	73°C/W
Storage temperature range, T_{stg}	−65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
 - The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
 - This current will flow only when the output is in the high state and $V_O > V_{DDQ}$.
 - The package thermal impedance is calculated in accordance with JESD 51.

SN74SSTL16847
20-BIT SSTL_3 INTERFACE BUFFER
WITH 3-STATE OUTPUTS

SCBS709A – OCTOBER 1997 – REVISED MAY 1998

recommended operating conditions (see Note 4)

		MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage	V _{DDQ}		3.6	V
V _{DDQ}	Output supply voltage	3		3.6	V
V _{REF}	Reference voltage (V _{REF} = 0.45 × V _{DDQ})	1.3	1.5	1.7	V
V _{TT}	Termination voltage	V _{REF} –50mV	V _{REF}	V _{REF} +50mV	V
V _I	Input voltage	0		V _{CC}	V
V _{IH}	AC high-level input voltage	All inputs		V _{REF} +400mV	V
V _{IL}	AC low-level input voltage	All inputs		V _{REF} –400mV	V
V _{IH}	DC high-level input voltage	All inputs		V _{REF} +200mV	V
V _{IL}	DC low-level input voltage	All inputs		V _{REF} –200mV	V
I _{OH}	High-level output current			–20	mA
I _{OL}	Low-level output current			20	
T _A	Operating free-air temperature	0		70	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{IK}		I _I = –18 mA	3 V			–1.2	V
V _{OH}		I _{OH} = –100 μA	3 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –16 mA	3 V	2.2			
		I _{OH} = –20 mA		2.1			
V _{OL}		I _{OL} = 100 μA	3 V to 3.6 V	0.2			V
		I _{OL} = 16 mA	3 V	0.5			
		I _{OL} = 20 mA		0.55			
I _I	Data inputs, $\overline{\text{OE}}$	V _I = 2.1 V or 0.9 V, V _{REF} = 1.3 V or 1.7 V	3.6 V	±5			μA
	V _{REF}	V _{REF} = 1.3 V or 1.7 V		±150			μA
I _{OZ}		V _O = 0.9 V or 2.1 V	3.6 V	±10			μA
I _{CC}		V _I = 2.1 V or 0.9 V, I _O = 0	3.6 V	90			mA
C _i	Control inputs	V _I = 2.1 V or 0.9 V	3.3 V	2			pF
	A port			2.5			
C _O	Y port	V _O = 2.1 V or 0.9 V	3.3 V	3.5			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

SN74SSTL16847
20-BIT SSTL_3 INTERFACE BUFFER
WITH 3-STATE OUTPUTS

SCBS709A – OCTOBER 1997 – REVISED MAY 1998

switching characteristics over recommended operating free-air temperature range,
Class I, $V_{REF} = V_{TT} = V_{DDQ} \times 0.45$ and $C_L = 10$ pF (unless otherwise noted) (see Figure 1)

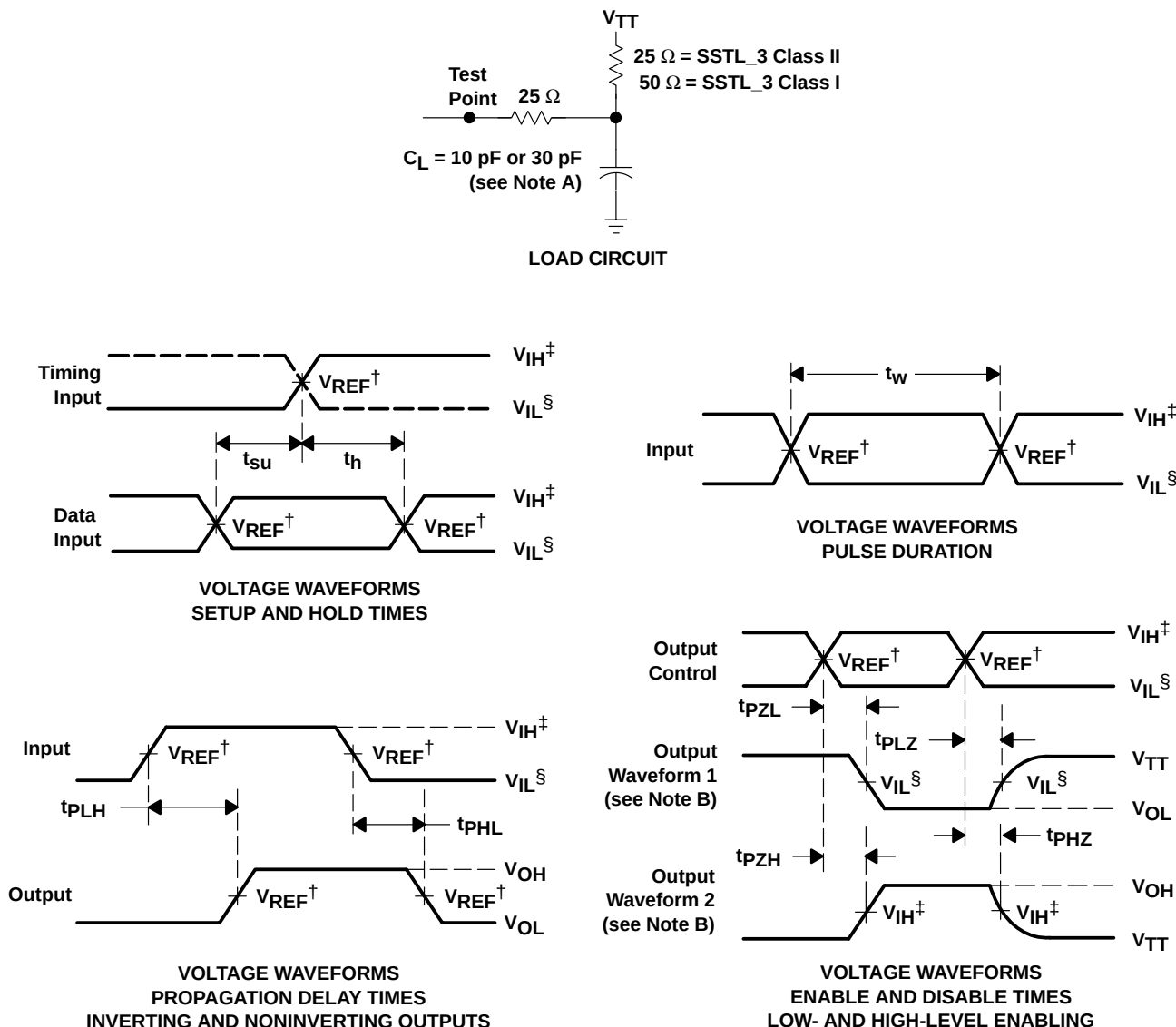
PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	MAX	UNIT
t_{pd}	A	Y	1.5	3	ns
t_{en}	$\overline{OE}$	Y	1.5	4	ns
t_{dis}	$\overline{OE}$	Y	1.6	4.9	ns

switching characteristics over recommended operating free-air temperature range,
Class II, $V_{REF} = V_{TT} = V_{DDQ} \times 0.45$ and $C_L = 30$ pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	MAX	UNIT
t_{pd}	A	Y	1.5	3	ns
t_{en}	$\overline{OE}$	Y	1.5	4.1	ns
t_{dis}	$\overline{OE}$	Y	1.5	4.8	ns



PARAMETER MEASUREMENT INFORMATION



$^\dagger V_{REF} = 0.45 V_{DDQ}$

$^\ddagger V_{IH} = V_{REF} + 400\text{mV}$ (AC voltage levels)

$^\S V_{IL} = V_{REF} - 400\text{mV}$ (AC voltage levels)

NOTES: A. C_L includes probe and jig capacitance.

B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\ \text{MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 1.25\ \text{ns/V}$, $t_f \leq 1.25\ \text{ns/V}$.

D. The outputs are measured one at a time with one transition per measurement.

E. $V_{TT} = V_{REF} = V_{DDQ} \times 0.45$

F. t_{pLZ} and t_{pHZ} are the same as t_{dis} .

G. t_{pZL} and t_{pZH} are the same as t_{en} .

H. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

- Member of the Texas Instruments *Widebus*™ Family
- Supports SSTL_2 Signal Data Inputs and Outputs
- Supports LVTTTL Switching Levels on the RESET Pin
- Differential CLK Signal
- Flow-Through Architecture Optimizes PCB Layout
- Meets SSTL_2 Class I and Class II Specifications
- Packaged in Plastic Thin Shrink Small-Outline Package

description

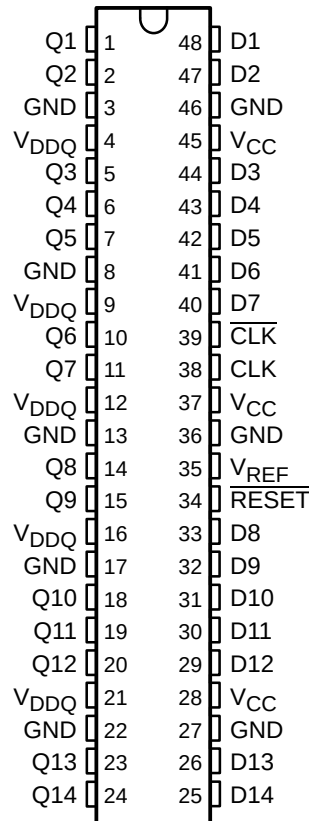
This 14-bit registered buffer is designed for 2.3-V to 3.6-V V_{CC} operation and SSTL_2 input and output levels.

Data flow from D to Q is controlled by differential clock pins (CLK, $\overline{\text{CLK}}$) and the RESET. Data are triggered on the positive edge of the positive clock (CLK). The negative clock ($\overline{\text{CLK}}$) must be used to maintain noise margins. When RESET is low, all registers are reset, and all outputs are low.

To ensure defined outputs from the register before a stable clock has been supplied, RESET must be held in the low state during power up.

The SN74SSTL16857 is characterized for operation from 0°C to 70°C.

DGG PACKAGE
(TOP VIEW)



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PRODUCT PREVIEW information concerns products in the formative or design phase of development. Characteristic data and other specifications are design goals. Texas Instruments reserves the right to change or discontinue these products without notice.



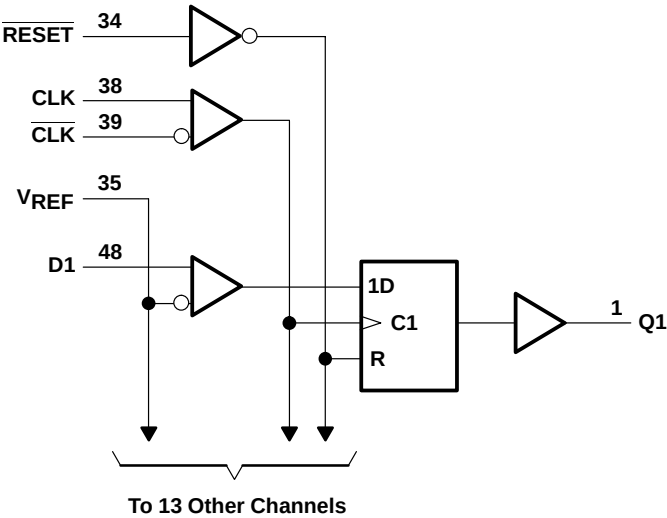
SN74SSTL16857
14-BIT SSTL_2 REGISTERED BUFFER

SCAS625 – FEBRUARY 1999

FUNCTION TABLE
(each flip-flop)

INPUTS				OUTPUT Q
RESET	CLK	CLK	D	
L	X	X	X	L
H	↓	↑	H	H
H	↓	↑	L	L
H	L or H	L or H	X	Q ₀

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC} or V_{DDQ}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to $V_{DDQ} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{DDQ} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O ($V_O = 0$ to V_{DDQ})	±50 mA
Continuous current through each V_{CC} , V_{DDQ} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3)	106°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
 2. This current will flow only when the output is in the high state and $V_O > V_{DDQ}$.
 3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage	V _{DDQ}		3.6	V
V _{DDQ}	Output supply voltage	2.3		2.7	V
V _{REF}	Reference voltage (V _{REF} = V _{DDQ} /2)	1.15	1.25	1.35	V
V _{TT}	Termination voltage	V _{REF} –40mV	V _{REF}	V _{REF} +40mV	V
V _I	Input voltage	0		V _{CC}	V
V _{IH}	AC high-level input voltage	Data inputs	V _{REF} +350mV		V
V _{IL}	AC low-level input voltage	Data inputs	V _{REF} –350mV		V
V _{IH}	DC high-level input voltage	Data inputs	V _{REF} +180mV		V
V _{IL}	DC low-level input voltage	Data inputs	V _{REF} –180mV		V
V _{IH}	High-level input voltage	Control inputs	2		V
V _{IL}	Low-level input voltage	Control inputs	0.8		V
V _{ICR}	Common-mode input voltage range	CLK, $\overline{\text{CLK}}$	0.97	1.53	V
V _{I(PP)}	Peak-to-peak input voltage	CLK, $\overline{\text{CLK}}$	360		mV
I _{OH}	High-level output current			–20	mA
I _{OL}	Low-level output current			20	
T _A	Operating free-air temperature	0		70	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

SN74SSTL16857

14-BIT SSTL_2 REGISTERED BUFFER

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		V _{CC}	MIN	TYP	MAX	UNIT	
V _{IK}		I _I = −18 mA		2.3 V			−1.2	V	
V _{OH}		I _{OH} = −100 μA		2.3 V to 2.7 V	V _{CC} −0.2			V	
		I _{OH} = −8 mA		2.3 V	1.95				
		I _{OH} = −16 mA			1.95				
V _{OL}		I _{OL} = 100 μA		2.3 V to 2.7 V	0.2			V	
		I _{OL} = 8 mA		2.3 V	0.35				
		I _{OL} = 16 mA			0.35				
I _I	Data inputs	V _I = 1.7 V or 0.8V		2.7 V	±5			μA	
		V _I = 2.7 V or 0			±5				
		V _I = 1.7 V or 0.8V		3.6 V	±5				
		V _I = 2.7 V or 0			±5				
	CLK, $\overline{\text{CLK}}$	V _I = 1.7 V or 0.8V		2.7 V	±5			μA	
		V _I = 2.7 V or 0			±5			mA	
		V _I = 1.7 V or 0.8V		3.6 V	±5			μA	
		V _I = 2.7 V or 0			±5			mA	
	$\overline{\text{RESET}}$	V _I = V _{CC} or GND			2.7 V	±5			μA
					3.6 V	±5			
	V _{REF}	V _{REF} = 1.15 V or 1.35 V			2.7 V	±5			μA
					3.6 V	±5			
I _{CC}		V _I = 1.7 V or 0.8 V		2.7 V	90			mA	
		V _I = 2.7 V or 0			90				
		V _I = 1.7 V or 0.8 V		3.6 V	90				
		V _I = 2.7 V or 0			90				
C _i	Control inputs	V _I = 1.7 V or 0.8 V			2.5 V [†]				pF
	Data inputs								
	Control inputs				3.3 V [‡]				
	Data inputs								

[†] All typical values are at V_{CC} = 2.5 V, T_A = 25°C.

[‡] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

PRODUCT PREVIEW



timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

			V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency						MHz
t _W	Pulse duration, CLK, $\overline{\text{CLK}}$ high or low						ns
t _{su}	Setup time	Data before CLK↑, $\overline{\text{CLK}}$ ↓					ns
		RESET high before CLK↑, $\overline{\text{CLK}}$ ↓					
t _h	Hold time, data after CLK↑, $\overline{\text{CLK}}$ ↓						ns

switching characteristics over recommended operating free-air temperature range, Class I, $V_{TT} = V_{REF} = V_{DDQ}/2$, and $C_L = 10\text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		UNIT
			MIN	MAX	MIN	MAX	
f_{max}							MHz
t_{pd}	CLK and $\overline{\text{CLK}}$	Q					ns
t_{PHL}	RESET	Q					ns

switching characteristics over recommended operating free-air temperature range, Class II, $V_{TT} = V_{REF} = V_{DDQ}/2$, and $C_L = 30\text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		UNIT
			MIN	MAX	MIN	MAX	
f_{max}							MHz
t_{pd}	CLK and $\overline{\text{CLK}}$	Q					ns
t_{PHL}	RESET	Q					ns

PRODUCT PREVIEW

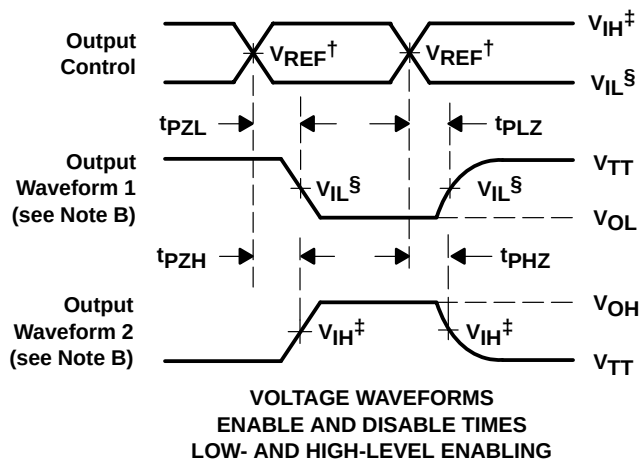
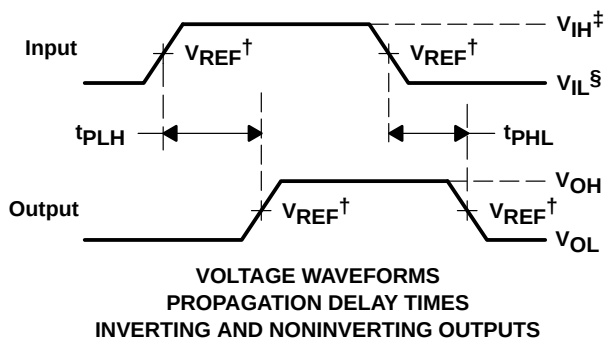
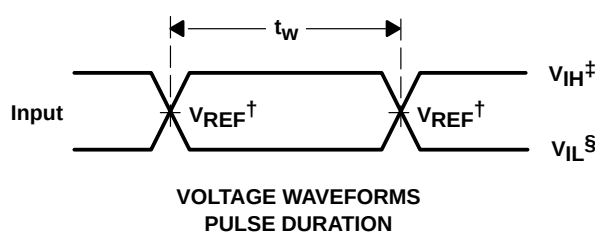
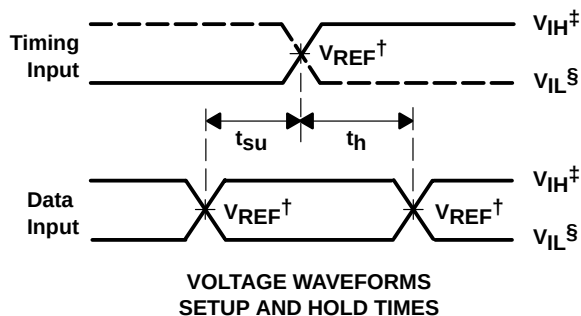
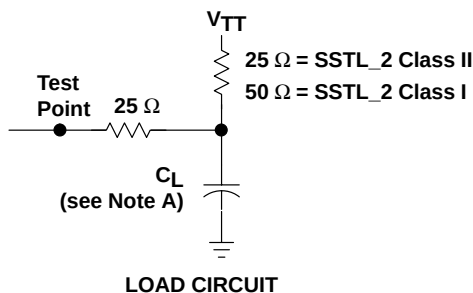
SN74SSTL16857

14-BIT SSTL_2 REGISTERED BUFFER

SCAS625 – FEBRUARY 1999

PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$ AND $V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$



† $V_{REF} = V_{DDQ}/2$

‡ $V_{IH} = V_{REF} + 350\text{ mV}$ (AC voltage levels)

§ $V_{IL} = V_{REF} - 350\text{ mV}$ (AC voltage levels)

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 1.25\text{ ns/V}$, $t_f \leq 1.25\text{ ns/V}$.
 - The outputs are measured one at a time with one transition per measurement.
 - $V_{TT} = V_{REF} = V_{DDQ}/2$
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms



- Member of the Texas Instruments *Widebus™* Family
- Supports SSTL_2 Signal Data Inputs
- Supports LVTTTL Switching Levels on the RESET Pin
- Flow-Through Architecture Optimizes PCB Layout
- Differential CLK Signal
- Advanced ULTTL Output Circuitry Eliminates Switching Noise in Unterminated Line
- Packaged in Plastic Fine-Pitch Ball-Grid-Array Package

description

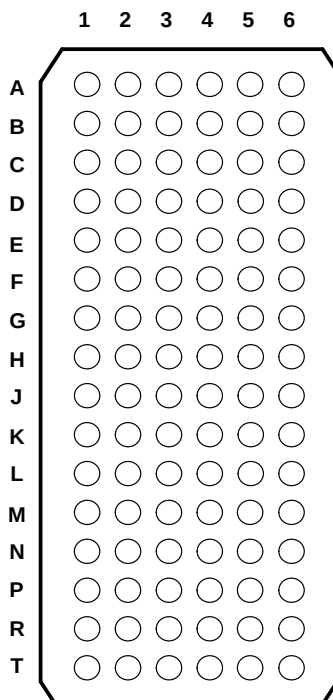
This 26-bit registered buffer is designed for 2.3-V to 2.7-V V_{CC} operation and SSTL_2 input and unterminated LVCMOS-output applications.

Data flow from A to Y is controlled by differential clock (CLK, $\overline{CLK}$) inputs and the LVTTTL reset ($\overline{RESET}$) input. Data are triggered on the positive edge of the positive clock (CLK). The negative clock ($\overline{CLK}$) is used to maintain noise margins. When $\overline{RESET}$ is low, all registers are reset, and all outputs are low.

To ensure defined outputs from the register before a stable clock has been supplied, $\overline{RESET}$ must be held in the low state during power up.

The SN74SSTL32867 is characterized for operation from 0°C to 70°C.

GKE PACKAGE
(TOP VIEW)



terminal assignments

	1	2	3	4	5	6
A	A1	V_{CC}	GND	V_{DDQ}	Y1	Y2
B	A3	A2	V_{REF}	GND	Y3	Y4
C	A5	A4	NC	GND	Y5	Y6
D	A7	A6	GND	V_{DDQ}	Y7	Y8
E	A9	A8	V_{CC}	GND	Y9	V_{DDQ}
F	A11	A10	GND	V_{DDQ}	Y10	GND
G	A13	A12	V_{CC}	V_{DDQ}	Y12	Y11
H	A15	A14	GND	GND	GND	Y13
J	CLK	NC	GND	GND	GND	Y14
K	$\overline{CLK}$	$\overline{RESET}$	V_{CC}	V_{DDQ}	Y15	Y16
L	A16	A17	GND	V_{DDQ}	Y17	GND
M	A18	A19	V_{CC}	GND	Y18	V_{DDQ}
N	A20	A21	GND	V_{DDQ}	Y20	Y19
P	A22	A23	NC	GND	Y22	Y21
R	A24	A25	NC	GND	Y24	Y23
T	A26	V_{CC}	GND	V_{DDQ}	Y26	Y25

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SN74SSTL32867
26-BIT REGISTERED BUFFER
WITH SSTL_2 INPUTS AND LVCMOS OUTPUTS

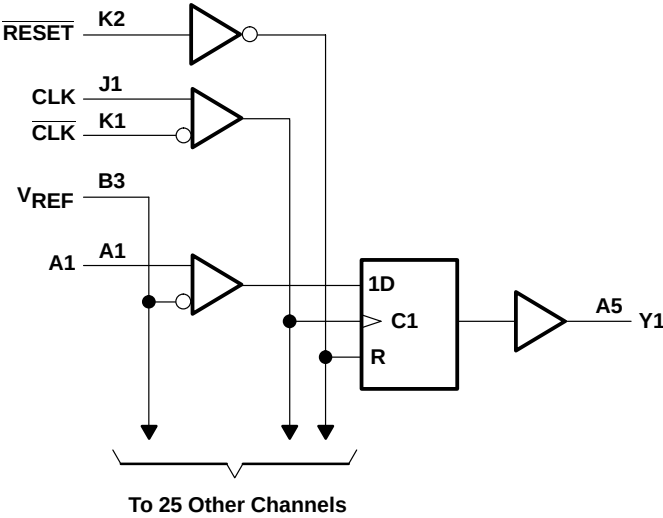
DESIGN GOAL

SCES240A – APRIL 1999 – REVISED MAY 1999

FUNCTION TABLE

INPUTS				OUTPUT Y
RESET	CLK	CLK	A	
H	↑	↓	H	H
H	↑	↓	L	L
H	L or H	L or H	X	Y_0
L	X	X	X	L

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC} or V_{DDQ}	–0.5 V to 3.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{DDQ} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O ($V_O = 0$ to V_{DDQ})	±50 mA
Continuous current through each V_{CC} , V_{DDQ} , or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3)	40°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
 2. Current flows only when the output is in the high state and $V_O > V_{DDQ}$.
 3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

			MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage		V _{DDQ}		2.7	V
V _{DDQ}	Output supply voltage		2.3		2.7	V
V _{REF}	Reference voltage (V _{REF} = V _{DDQ} /2)		1.15	1.25	1.35	V
V _{TT}	Termination voltage		V _{REF} –40mV	V _{REF}	V _{REF} +40mV	V
V _I	Input voltage		0		V _{CC}	V
V _{IH}	AC high-level input voltage	Data input	V _{REF} +350mV			V
V _{IL}	AC low-level input voltage	Data input	V _{REF} –350mV			V
V _{IH}	DC high-level input voltage	Data input	V _{REF} +180mV			V
V _{IL}	DC low-level input voltage	Data input	V _{REF} –180mV			V
V _{IH}	High-level input voltage	RESET	1.7			V
V _{IL}	Low-level input voltage	RESET	0.7			V
V _{ICR}	Common-mode input voltage range	CLK, CLK	0.97		1.53	V
V _{I(PP)}	Peak-to-peak input voltage	CLK, CLK	360			mV
I _{OH}	High-level output current		–8			mA
I _{OL}	Low-level output current		8			
T _A	Operating free-air temperature		0		70	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{IK}		I _I = –18 mA		2.3 V			–1.2	V
V _{OH}		I _{OH} = –100 μA		2.3 V to 2.7 V	V _{CC} –0.2			V
		I _{OH} = –4 mA		2.3 V	2			
		I _{OH} = –8 mA			1.7			
V _{OL}		I _{OL} = 100 μA		2.3 V to 2.7 V	0.2		V	
		I _{OL} = 4 mA		2.3 V	0.3			
		I _{OL} = 8 mA			0.6			
I _I	Data inputs	V _I = 1.7 V or 0.8V	V _{REF} = 1.15 V or 1.35 V	2.7 V			±5	μA
	RESET input	V _I = 2.7 V or 0					±5	
	CLK, CLK	V _I = 1.7 V or 0.8V	V _{REF} = 1.15 V or 1.35 V	2.7 V			±5	
		V _I = 2.7 V or 0					±5	
	V _{REF}	V _{REF} = 1.15 V or 1.35 V		2.7 V			±5	
I _{CC}		V _I = 1.7 V or 0.8 V	I _O = 0	2.7 V			mA	
		V _I = 2.7 V or 0						
C _i	RESET input	V _I = 1.7 V or 0.8 V		2.5 V [†]			pF	
	Data inputs							
C _O	Outputs	V _O = 1.7 V or 0.8 V		2.5 V [†]			pF	

[†] All typical values are at V_{CC} = 2.5 V, T_A = 25°C.

SN74SSTL32867
26-BIT REGISTERED BUFFER
WITH SSTL_2 INPUTS AND LVCMOS OUTPUTS

DESIGN GOAL

SCES240A – APRIL 1999 – REVISED MAY 1999

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

			$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$			UNIT
			MIN	TYP	MAX	
f_{clock}	Clock frequency		200			MHz
t_w	Pulse duration, CLK, $\overline{\text{CLK}}$ high or low		1.6	0.8		ns
t_{su}	Setup time	Data before $\text{CLK}\uparrow$, $\overline{\text{CLK}}\downarrow$	1.1	0.5		ns
		$\overline{\text{RESET}}$ high before $\text{CLK}\uparrow$, $\overline{\text{CLK}}\downarrow$	1.1	0.5		
t_h	Hold time, data after $\text{CLK}\uparrow$, $\overline{\text{CLK}}\downarrow$		0.5	0		ns

switching characteristics over recommended operating free-air temperature range,
 $V_{\text{REF}} = V_{\text{DDQ}}/2$ and $C_L = 10\text{ pF}$ (unless otherwise noted) (see Figure 1)

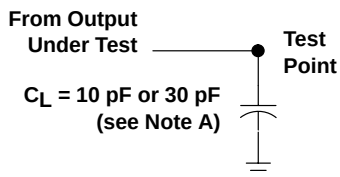
PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$			UNIT
			MIN	TYP	MAX	
f_{max}					200	MHz
t_{pd}	CLK and $\overline{\text{CLK}}$	Y		1.9	2.8	ns
t_{PHL}	$\overline{\text{RESET}}$	Y		2.2	3.2	ns

switching characteristics over recommended operating free-air temperature range,
 $V_{\text{REF}} = V_{\text{DDQ}}/2$ and $C_L = 30\text{ pF}$ (unless otherwise noted) (see Figure 1)

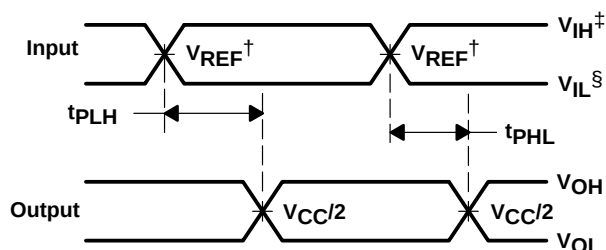
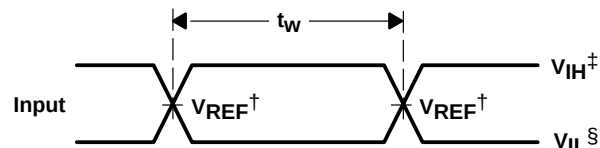
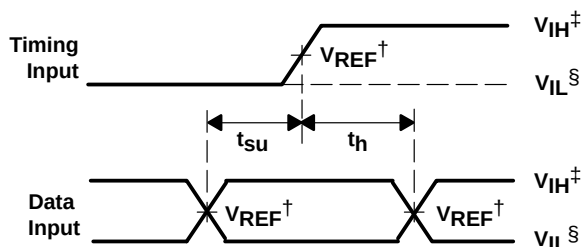
PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$			UNIT
			MIN	TYP	MAX	
f_{max}					200	MHz
t_{pd}	CLK and $\overline{\text{CLK}}$	Y		2.6	3.8	ns
t_{PHL}	$\overline{\text{RESET}}$	Y		2.9	4.4	ns

PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$$



LOAD CIRCUIT

VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES
NONINVERTING OUTPUTSVOLTAGE WAVEFORMS
PULSE DURATIONVOLTAGE WAVEFORMS
SETUP AND HOLD TIMES

$^{\dagger} V_{REF} = V_{DDQ}/2$

$^{\ddagger} V_{IH} = V_{REF} + 350\text{ mV}$ (ac voltage levels) for SSTL inputs. $V_{IH} = V_{CC}$ for LVTTTL inputs.

$^{\S} V_{IL} = V_{REF} - 350\text{ mV}$ (ac voltage levels) for SSTL inputs. $V_{IL} = \text{GND}$ for LVTTTL inputs.

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. All input pulses are supplied by generators having the following characteristics: $\text{PRR} \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 1.25\text{ ns/V}$, $t_f \leq 1.25\text{ ns/V}$.
 - C. The outputs are measured one at a time with one transition per measurement.
 - D. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

- Member of the Texas Instruments *Widebus™* Family
- Supports SSTL_2 Signal Data Inputs and Outputs
- Supports LVTTTL Switching Levels on the RESET Pin
- Flow-Through Architecture Optimizes PCB Layout
- Differential CLK Signal
- Meets SSTL_2 Class I and Class II Specifications
- Packaged in Plastic Fine-Pitch Ball-Grid-Array Package

description

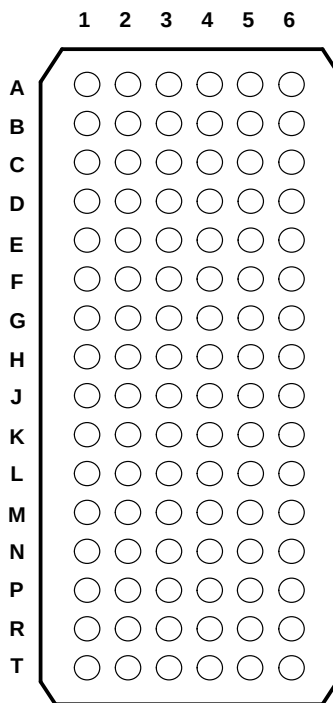
This 26-bit registered buffer is designed for 2.3-V to 2.7-V V_{CC} operation and SSTL_2 input and output levels.

Data flow from A to Y is controlled by differential clock (CLK, $\overline{CLK}$) inputs, the SSTL_2 output-enable ($\overline{OE}$) input, and the LVTTTL reset ($\overline{RESET}$) input. Data are triggered on the positive edge of the positive clock (CLK). The negative clock ($\overline{CLK}$) must be used to maintain noise margins. When $\overline{RESET}$ is low, all registers are reset, and all outputs are low.

To ensure defined outputs from the register before a stable clock has been supplied, $\overline{RESET}$ must be held in the low state during power up.

The SN74SSTL32877 is characterized for operation from 0°C to 70°C.

GKE PACKAGE
(TOP VIEW)



terminal assignments

	1	2	3	4	5	6
A	A1	V_{CC}	GND	V_{DDQ}	Y1	Y2
B	A3	A2	V_{REF}	GND	Y3	Y4
C	A5	A4	NC	GND	Y5	Y6
D	A7	A6	GND	V_{DDQ}	Y7	Y8
E	A9	A8	V_{CC}	GND	Y9	V_{DDQ}
F	A11	A10	GND	V_{DDQ}	Y10	GND
G	A13	A12	V_{CC}	V_{DDQ}	Y12	Y11
H	A15	A14	GND	GND	GND	Y13
J	CLK	NC	GND	GND	GND	Y14
K	$\overline{CLK}$	$\overline{RESET}$	V_{CC}	V_{DDQ}	Y15	Y16
L	A16	A17	GND	V_{DDQ}	Y17	GND
M	A18	A19	V_{CC}	GND	Y18	V_{DDQ}
N	A20	A21	GND	V_{DDQ}	Y20	Y19
P	A22	A23	NC	GND	Y22	Y21
R	A24	A25	$\overline{OE}$	GND	Y24	Y23
T	A26	V_{CC}	GND	V_{DDQ}	Y26	Y25

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PRODUCT PREVIEW information concerns products in the formative or design phase of development. Characteristic data and other specifications are design goals. Texas Instruments reserves the right to change or discontinue these products without notice.



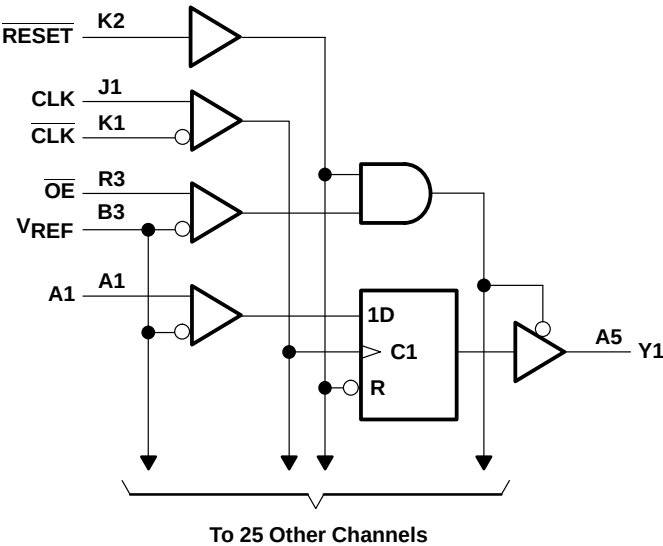
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FUNCTION TABLE

INPUTS					OUTPUT Y
OE	RESET	CLK	CLK	A	
L	H	↑	↓	H	H
L	H	↑	↓	L	L
L	H	L or H	L or H	X	Y ₀
H	H	X	X	X	Z
X	L	X	X	X	L

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC} or V_{DDQ}	–0.5 V to 3.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{DDQ} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O ($V_O = 0$ to V_{DDQ})	±50 mA
Continuous current through each V_{CC} , V_{DDQ} , or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3)	40°C/W
Storage temperature range, T_{Stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
 2. Current flows only when the output is in the high state and $V_O > V_{DDQ}$.
 3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

			MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage		V _{DDQ}		2.7	V
V _{DDQ}	Output supply voltage		2.3		2.7	V
V _{REF}	Reference voltage (V _{REF} = V _{DDQ} /2)		1.15	1.25	1.35	V
V _{TT}	Termination voltage		V _{REF} –40mV	V _{REF}	V _{REF} +40mV	V
V _I	Input voltage		0		V _{CC}	V
V _{IH}	AC high-level input voltage	$\overline{OE}$, data inputs	V _{REF} +350mV			V
V _{IL}	AC low-level input voltage	$\overline{OE}$, data inputs	V _{REF} –350mV			V
V _{IH}	DC high-level input voltage	$\overline{OE}$, data inputs	V _{REF} +180mV			V
V _{IL}	DC low-level input voltage	$\overline{OE}$, data inputs	V _{REF} –180mV			V
V _{IH}	High-level input voltage	$\overline{RESET}$	1.7			V
V _{IL}	Low-level input voltage	$RESET$	0.7			V
V _{ICR}	Common-mode input voltage range	CLK, $\overline{CLK}$	0.97		1.53	V
V _{I(PP)}	Peak-to-peak input voltage	CLK, $\overline{CLK}$	360			mV
I _{OH}	High-level output current		–20			mA
I _{OL}	Low-level output current		20			
T _A	Operating free-air temperature		0		70	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{IK}		I _I = –18 mA		2.3 V			–1.2	V
V _{OH}		I _{OH} = –100 μA		2.3 V to 2.7 V	V _{CC} –0.2			V
		I _{OH} = –8 mA		2.3 V	1.95			
		I _{OH} = –16 mA			1.95			
V _{OL}		I _{OL} = 100 μA		2.3 V to 2.7 V			0.2	V
		I _{OL} = 8 mA		2.3 V			0.35	
		I _{OL} = 16 mA					0.35	
I _I	Data inputs	V _I = 1.7 V or 0.8V	V _{REF} = 1.15 V or 1.35 V	2.7 V			±5	μA
	$\overline{\text{OE}}$ input	V _I = 2.7 V or 0					±5	
	$\overline{\text{RESET}}$ input	V _I = 2.7 V or 0					±5	
	CLK, $\overline{\text{CLK}}$	V _I = 1.7 V or 0.8V	V _{REF} = 1.15 V or 1.35 V				±5	
		V _I = 2.7 V or 0					±5	
	V _{REF}	V _{REF} = 1.15 V or 1.35 V					±5	
I _{CC}		V _I = 1.7 V or 0.8 V	I _O = 0	2.7 V			mA	
		V _I = 2.7 V or 0						
C _i	$\overline{\text{RESET}}$ input	V _I = 1.7 V or 0.8 V		2.5 V [†]			pF	
	Data inputs							
C _O	Outputs	V _O = 1.7 V or 0.8 V		2.5 V [†]			pF	

[†] All typical values are at V_{CC} = 2.5 V, T_A = 25°C.

SN74SSTL32877
26-BIT REGISTERED BUFFER
WITH SSTL_2 INPUTS AND OUTPUTS

SCES241A – APRIL 1999 – REVISED MAY 1999

DESIGN GOAL

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

			$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$			UNIT
			MIN	TYP	MAX	
f_{clock}	Clock frequency		200			MHz
t_w	Pulse duration, CLK, $\overline{\text{CLK}}$ high or low		1.6	0.8		ns
t_{su}	Setup time	Data before CLK $\uparrow$, $\overline{\text{CLK}}$ $\downarrow$	1.1	0.5		ns
		$\overline{\text{RESET}}$ high before CLK $\uparrow$, $\overline{\text{CLK}}$ $\downarrow$	1.1	0.5		
t_h	Hold time, data after CLK $\uparrow$, $\overline{\text{CLK}}$ $\downarrow$		0.5	0		ns

switching characteristics over recommended operating free-air temperature range,
Class I, $V_{TT} = V_{REF} = V_{DDQ}/2$, and $C_L = 10\text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$			UNIT
			MIN	TYP	MAX	
f_{max}					200	MHz
t_{pd}	CLK and $\overline{\text{CLK}}$	Y		1.7	2.5	ns
t_{PHL}	$\overline{\text{RESET}}$	Y		2.4	3.5	ns
t_{en}	$\overline{\text{OE}}$	Y		2.6	3.8	ns
t_{dis}	$\overline{\text{OE}}$	Y		2.6	3.8	ns

switching characteristics over recommended operating free-air temperature range,
Class II, $V_{TT} = V_{REF} = V_{DDQ}/2$ and $C_L = 30\text{ pF}$ (unless otherwise noted) (see Figure 1)

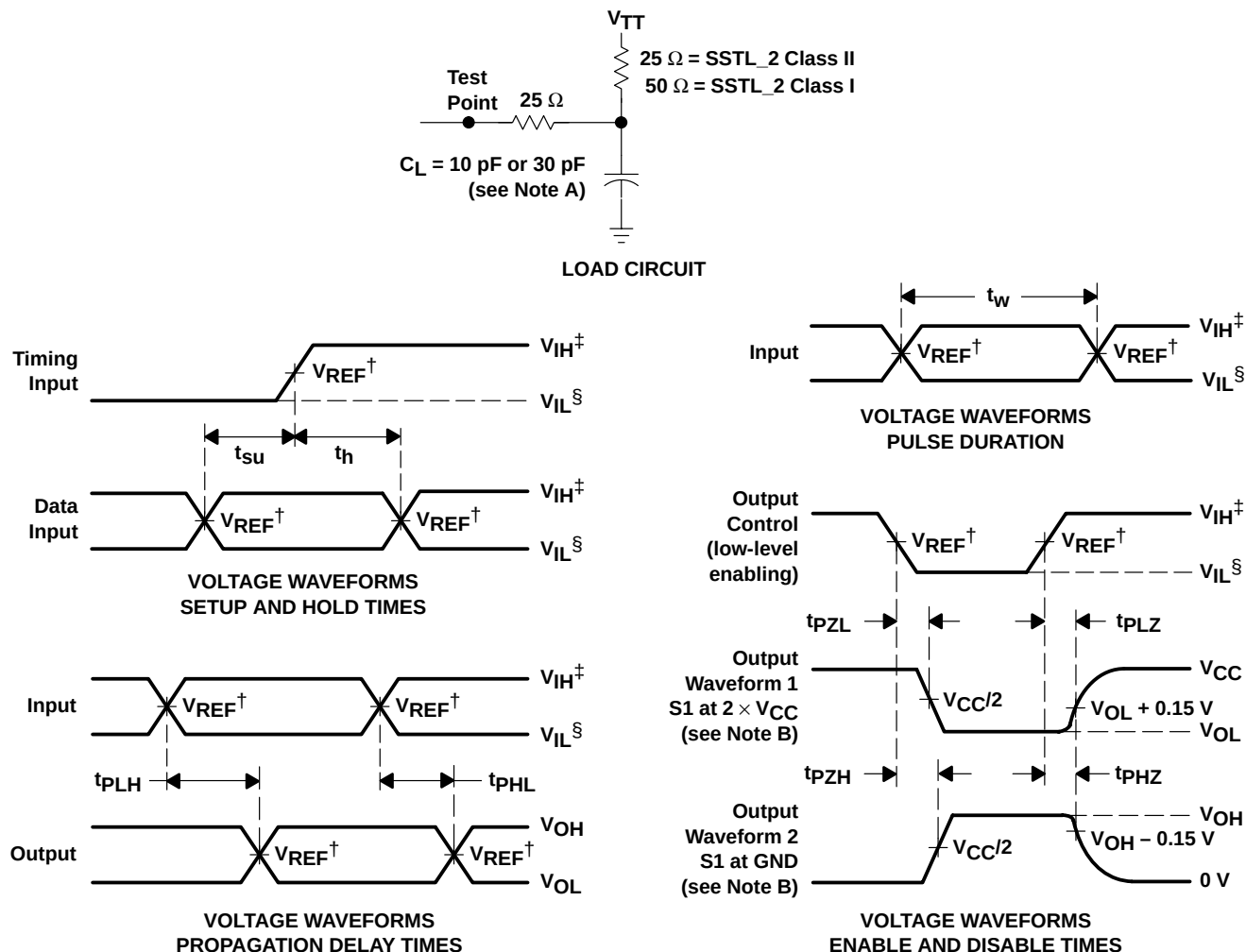
PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$			UNIT
			MIN	TYP	MAX	
f_{max}					200	MHz
t_{pd}	CLK and $\overline{\text{CLK}}$	Y		1.7	2.5	ns
t_{PHL}	$\overline{\text{RESET}}$	Y		2.4	3.5	ns
t_{en}	$\overline{\text{OE}}$	Y		2.6	3.8	ns
t_{dis}	$\overline{\text{OE}}$	Y		2.6	3.8	ns

PRODUCT PREVIEW



PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$



$^\dagger V_{REF} = V_{DDQ}/2$

$^\ddagger V_{IH} = V_{REF} + 350 \text{ mV}$ (ac voltage levels) for SSTL inputs. $V_{IH} = V_{CC}$ for LVTTTL inputs.

$^\S V_{IL} = V_{REF} - 350 \text{ mV}$ (ac voltage levels) for SSTL inputs. $V_{IL} = \text{GND}$ for LVTTTL inputs.

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $\text{PRR} \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. $V_{TT} = V_{REF} = V_{DDQ}/2$
 - F. t_{pLZ} and t_{pHZ} are the same as t_{dis} .
 - G. t_{pZL} and t_{pZH} are the same as t_{en} .
 - H. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

General Information	1
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SN74HSTL16918 9-BIT TO 18-BIT HSTL-TO-LVTTL MEMORY ADDRESS LATCH

SCES096C – APRIL 1997 – REVISED JANUARY 1999

- Member of the Texas Instruments Widebus™ Family
- Inputs Meet JEDEC HSTL Std JESD 8-6 and Outputs Meet Level III Specifications
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Packaged in Plastic Thin Shrink Small-Outline Package

description

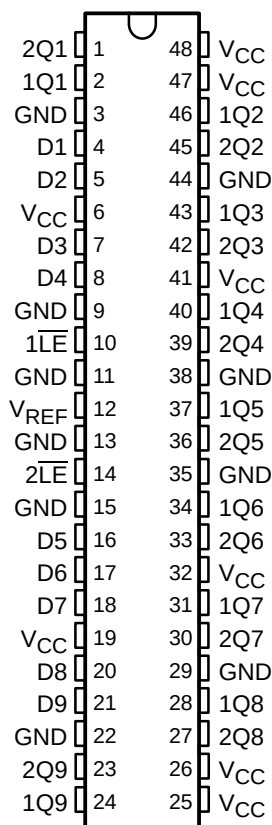
This 9-bit to 18-bit D-type latch is designed for 3.15-V to 3.45-V V_{CC} operation. The D inputs accept HSTL levels and the Q outputs provide LVTTL levels.

The SN74HSTL16918 is particularly suitable for driving an address bus to two banks of memory. Each bank of nine outputs is controlled with its own latch-enable ($\overline{LE}$) input.

Each of the nine D inputs is tied to the inputs of two D-type latches that provide true data (Q) at the outputs. While $\overline{LE}$ is low, the Q outputs of the corresponding nine latches follow the D inputs. When $\overline{LE}$ is taken high, the Q outputs are latched at the levels set up at the D inputs.

The SN74HSTL16918 is characterized for operation from 0°C to 70°C.

DGG PACKAGE
(TOP VIEW)



FUNCTION TABLE

INPUTS		OUTPUT
$\overline{LE}$	D	Q
L	H	H
L	L	L
H	X	$Q_0^\dagger$

[†] Output level before the indicated steady-state input conditions were established

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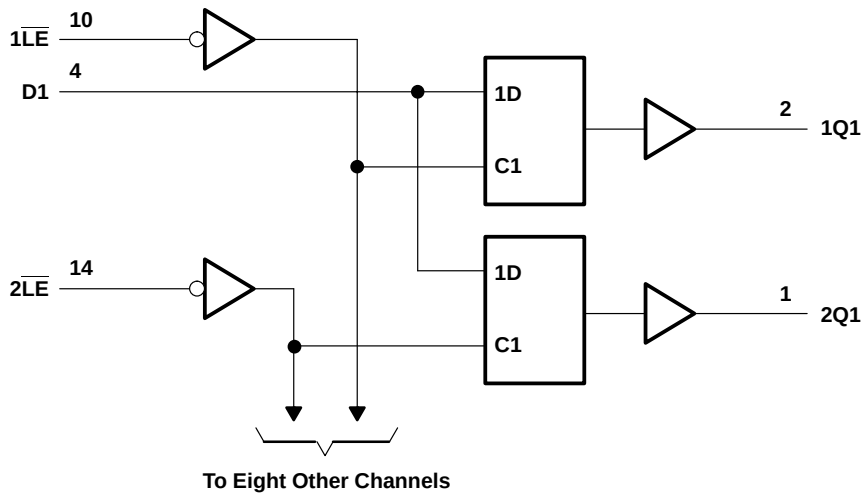
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SN74HSTL16918
9-BIT TO 18-BIT HSTL-TO-LVTTL MEMORY ADDRESS LATCH

SCES096C – APRIL 1997 – REVISED JANUARY 1999

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Note 1)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) (see Note 2)	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3)	89°C/W
Storage temperature range, T_{Stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
 2. This current flows only when the output is in the high state and $V_O > V_{CC}$.
 3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage	3.15		3.45	V
V_{REF}	Reference voltage	0.68	0.75	0.9	V
V_I	Input voltage	0		1.5	V
V_{IH}	AC high-level input voltage	All inputs		$V_{REF} + 200$ mV	V
V_{IL}	AC low-level input voltage	All inputs		$V_{REF} - 200$ mV	V
V_{IH}	DC high-level input voltage	All inputs		$V_{REF} + 100$ mV	V
V_{IL}	DC low-level input voltage	All inputs		$V_{REF} - 100$ mV	V
I_{OH}	High-level output current			–24	mA
I_{OL}	Low-level output current			24	mA
T_A	Operating free-air temperature	0		70	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



SN74HSTL16918

9-BIT TO 18-BIT HSTL-TO-LVTTL MEMORY ADDRESS LATCH

SCES096C – APRIL 1997 – REVISED JANUARY 1999

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP [†]	MAX	UNIT
V_{IK}		$V_{CC} = 3.15\text{ V}$, $I_I = -18\text{ mA}$			-1.2	V
V_{OH}		$V_{CC} = 3.15\text{ V}$, $I_{OH} = -24\text{ mA}$	2.4			V
V_{OL}		$V_{CC} = 3.15\text{ V}$, $I_{OL} = 24\text{ mA}$			0.5	V
I_I	Control inputs	$V_{CC} = 3.45\text{ V}$	$V_I = 0\text{ or }1.5\text{ V}$		±5	μA
	Data inputs		$V_I = 0\text{ or }1.5\text{ V}$		±5	
	V_{REF}		$V_{REF} = 0.68\text{ V or }0.9\text{ V}$		90	
I_{CC}		$V_{CC} = 3.45\text{ V}$, $V_I = 0\text{ or }1.5\text{ V}$		50	100	mA
C_i	Control inputs	$V_{CC} = 0\text{ or }3.3\text{ V}$, $V_I = 0\text{ or }3.3\text{ V}$		2		pF
	Data inputs	$V_{CC} = 0\text{ or }3.3\text{ V}$, $V_I = 0\text{ or }3.3\text{ V}$		2.5		
C_o	Outputs	$V_{CC} = 0$, $V_O = 0$		4		pF

[†] All typical values are at $V_{CC} = 3.3\text{ V}$, $T_A = 25^\circ\text{C}$.

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

		$V_{CC} = 3.3\text{ V}$ $\pm 0.15\text{ V}$	UNIT
		MIN MAX	
t_w	Pulse duration, $\overline{LE}$ low	3	ns
t_{su}	Setup time, D before $\overline{LE}\uparrow$	2	ns
t_h	Hold time	D after $\overline{LE}\uparrow$	1 ns
$t_{ldr}^\ddagger$	Data race condition time	D after $\overline{LE}\downarrow$	0 ns

[‡] This is the maximum time after $\overline{LE}$ switches low that the data input can return to the latched state from the opposite state without producing a glitch on the output.

switching characteristics over recommended operating free-air temperature range, $V_{REF} = 0.75\text{ V}$

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 3.3\text{ V}$ $\pm 0.15\text{ V}$		UNIT
			MIN	MAX	
t_{pd}	D	Q	1.9	3.4	ns
	$\overline{LE}$		1.9	4.2	

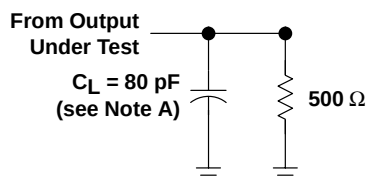
simultaneous switching characteristics over recommended operating free-air temperature range, $V_{REF} = 0.75\text{ V}^\S$

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 3.3\text{ V}$ $\pm 0.15\text{ V}$		UNIT
			MIN	MAX	
t_{pd}	D	Q	1.9	4.4	ns
	$\overline{LE}$		1.9	5.2	

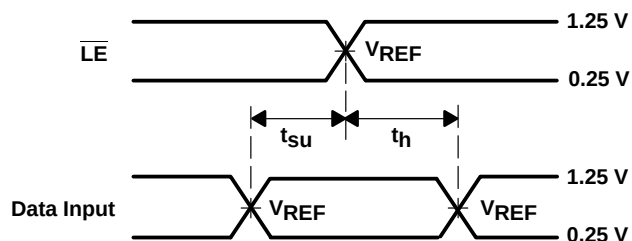
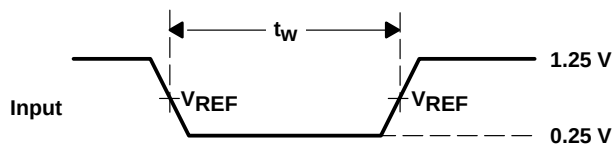
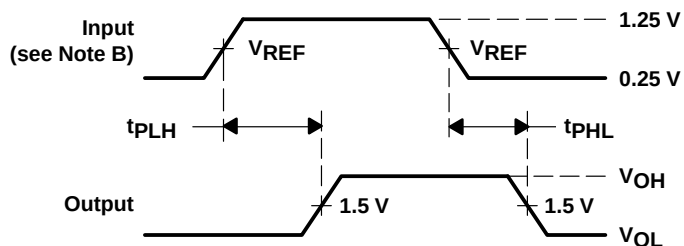
[§] All outputs switching



PARAMETER MEASUREMENT INFORMATION



LOAD CIRCUIT

VOLTAGE WAVEFORMS
SETUP AND HOLD TIMESVOLTAGE WAVEFORMS
PULSE DURATIONVOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES

- NOTES: A. C_L includes probe and jig capacitance.
B. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 1 \text{ ns}$, $t_f \leq 1 \text{ ns}$.
C. The outputs are measured one at a time with one transition per measurement.
D. t_{PHL} and t_{PLH} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74HSTL162822

14-BIT TO 28-BIT HSTL-TO-LVTTL MEMORY ADDRESS LATCH

SCES091A – DECEMBER 1996 – REVISED APRIL 1997

- Member of the Texas Instruments Widebus™ Family
- Inputs Meet JEDEC HSTL Standard JESD8-6
- All Outputs Have Equivalent 25-Ω Series Resistors
- Packaged in Plastic Thin Shrink Small-Outline Package

description

This 14-bit to 28-bit D-type latch is designed for 3.15-V to 3.45-V V_{CC} operation. HSTL levels are expected on the inputs. LVTTL levels are driven on the Q outputs.

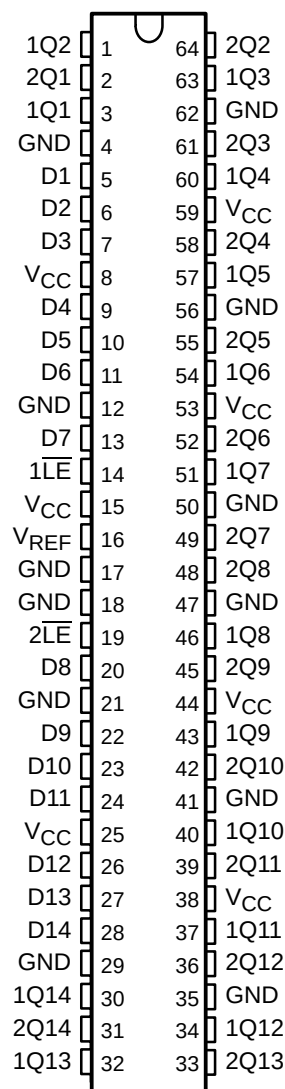
All outputs are designed to sink up to 12 mA and include 25-Ω series resistors to reduce overshoot and undershoot.

The SN74HSTL162822 is particularly suitable for driving an address bus to two banks of memory. Each bank of 14 outputs is controlled with its own latch-enable ($\overline{LE}$) input.

Each of the 14 data (D) inputs is tied to the inputs of two D-type latches, which provide true data at the outputs. While $\overline{LE}$ is low, the outputs (Q) of the corresponding 14 latches follow the D inputs. When $\overline{LE}$ is taken high, the Q outputs are latched at the levels set up at the D inputs.

The SN74HSTL162822 is characterized for operation from -40°C to 90°C.

DGG PACKAGE
(TOP VIEW)



FUNCTION TABLE

INPUTS		OUTPUT
$\overline{LE}$	D	Q
L	H	H
L	L	L
H	X	$Q_0^\dagger$

[†] Output level before the indicated steady-state input conditions were established

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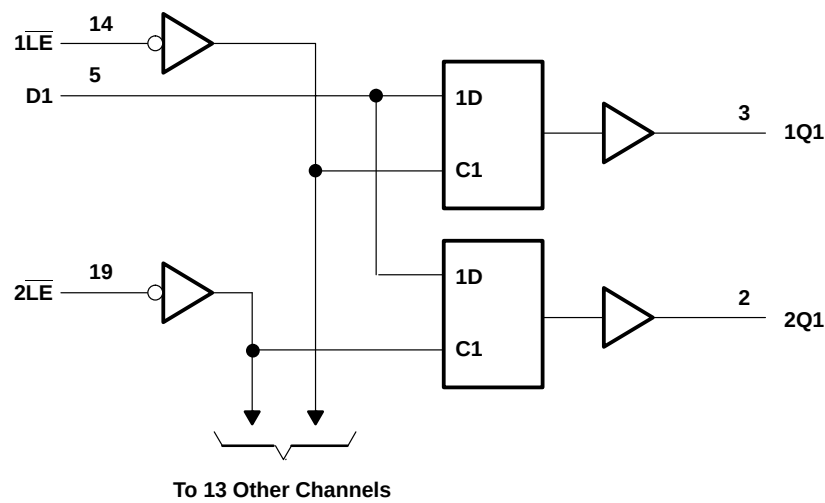
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SN74HSTL162822
14-BIT TO 28-BIT HSTL-TO-LVTTL MEMORY ADDRESS LATCH

SCES091A – DECEMBER 1996 – REVISED APRIL 1997

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Table with 2 columns: Parameter and Rating. Parameters include Supply voltage range, Input voltage range, Output voltage range, Input clamp current, Output clamp current, Continuous output current, Continuous current through each VCC or GND, Package thermal impedance, and Storage temperature range.

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
- 2. This current flows only when the output is in the high state and VO > VCC.
- 3. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51.

recommended operating conditions (see Note 4)

Table with 5 columns: Parameter, Description, MIN, NOM, MAX, UNIT. Parameters include VCC, VREF, VI, VIH, VIL, IOH, IOL, and TA.

NOTE 4: Unused inputs must be held high or low to prevent them from floating.

SN74HSTL162822

14-BIT TO 28-BIT HSTL-TO-LVTTL MEMORY ADDRESS LATCH

SCES091A – DECEMBER 1996 – REVISED APRIL 1997

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP [†]	MAX	UNIT
V_{IK}		$V_{CC} = 3.15\text{ V}$, $I_I = -18\text{ mA}$			-1.2	V
V_{OH}		$V_{CC} = 3.15\text{ V}$, $I_{OH} = -12\text{ mA}$	2.2			V
V_{OL}		$V_{CC} = 3.15\text{ V}$, $I_{OL} = 12\text{ mA}$			0.8	V
I_I	Control inputs	$V_{CC} = 3.45\text{ V}$	$V_I = 0\text{ or }1.5\text{ V}$		5	μA
	Data inputs		$V_I = 0\text{ or }1.5\text{ V}$		5	
	V_{REF}		$V_{REF} = 0.68\text{ V or }0.9\text{ V}$		90	
I_{CC}		$V_{CC} = 3.45\text{ V}$, $V_I = 0\text{ or }1.5\text{ V}$		50	100	mA
C_i	Control inputs	$V_{CC} = 0\text{ or }3.3\text{ V}$, $V_I = 0\text{ or }3.3\text{ V}$	2			pF
	Data inputs	$V_{CC} = 0\text{ or }3.3\text{ V}$, $V_I = 0\text{ or }3.3\text{ V}$	2			
C_o	Outputs	$V_{CC} = 0$, $V_O = 0$	4			pF

[†] All typical values are at $V_{CC} = 3.3\text{ V}$, $T_A = 25^\circ\text{C}$.

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

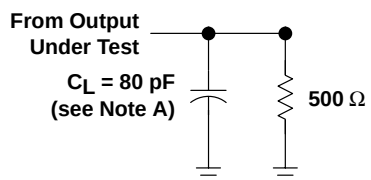
		$V_{CC} = 3.3\text{ V} \pm 0.15\text{ V}$		UNIT
		MIN	MAX	
t_w	Pulse duration, $\overline{LE}$ low	3		ns
t_{su}	Setup time, D before $\overline{LE}\uparrow$	2		ns
t_h	Hold time, D after $\overline{LE}\uparrow$	1		ns

switching characteristics over recommended operating free-air temperature range, $V_{REF} = 0.75\text{ V}$

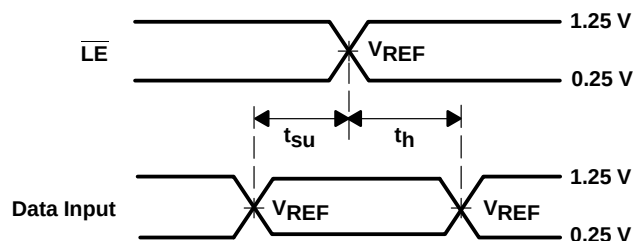
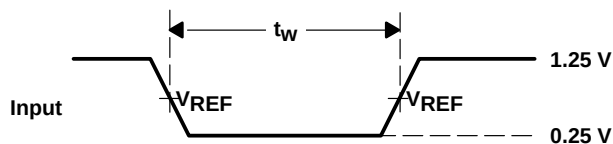
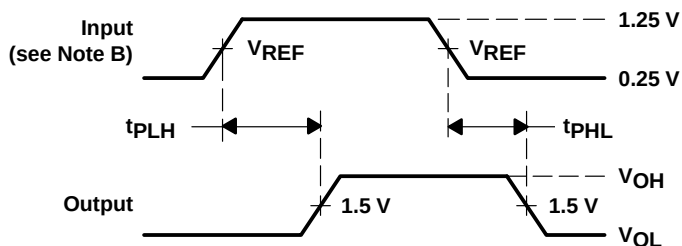
PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 3.3\text{ V} \pm 0.15\text{ V}$		UNIT
			MIN	MAX	
t_{pd}	D	Q	1.6	5	ns
	$\overline{LE}$		1.7	5.7	



PARAMETER MEASUREMENT INFORMATION



LOAD CIRCUIT

VOLTAGE WAVEFORMS
SETUP AND HOLD TIMESVOLTAGE WAVEFORMS
PULSE DURATIONVOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES

- NOTES: A. C_L includes probe and jig capacitance.
- B. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 1 \text{ ns}$, $t_f \leq 1 \text{ ns}$.
- C. The outputs are measured one at a time with one transition per measurement.
- D. t_{PHL} and t_{PLH} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

General Information	1
ALVC Gates/Octals	2
ALVC Widebus™/Widebus+™	3
ALVC Widebus™ With Series Damping Resistors	4
ALVC Dual-Supply-Voltage Translators	5
SSTL	6
HSTL	7
ALB	8
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SN74ALB16245 3.3-V ALB 16-Bit Transceiver With 3-State Outputs	8–9

SN74ALB16244

16-BIT BUFFER/DRIVER WITH 3-STATE OUTPUTS

SCBS647C – AUGUST 1995 – REVISED JULY 1997

- Member of the Texas Instruments *Widebus*™ Family
- State-of-the-Art Advanced Low-Voltage BiCMOS (ALB) Technology Design for 3.3-V Operation
- Schottky Diodes on All Inputs to Eliminate Overshoot and Undershoot
- Industry Standard '16244 Pinout
- Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB Layout
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

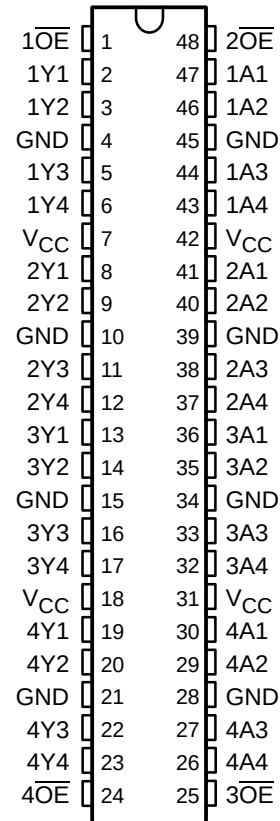
description

The SN74ALB16244 16-bit buffer and line driver is designed for high-speed, low-voltage (3.3-V) V_{CC} operation. This device is intended to replace the conventional driver in any speed-critical path. The small propagation delay is achieved using a unity gain amplifier on the input and feedback resistors from input to output, which allows the output to track the input with a small offset voltage.

The device can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. This device provides true outputs and symmetrical active-low output-enable ($\overline{\text{OE}}$) inputs.

The SN74ALB16244 is characterized for operation from –40°C to 85°C.

DGG OR DL PACKAGE (TOP VIEW)



FUNCTION TABLE
(each buffer)

INPUTS		OUTPUT Y
$\overline{\text{OE}}$	A	
L	H	H
L	L	L
H	X	Z

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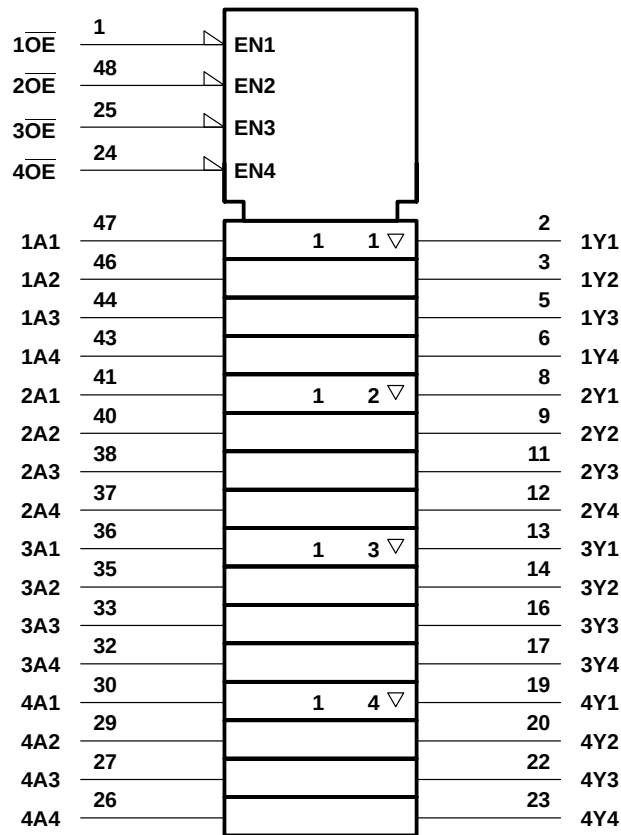
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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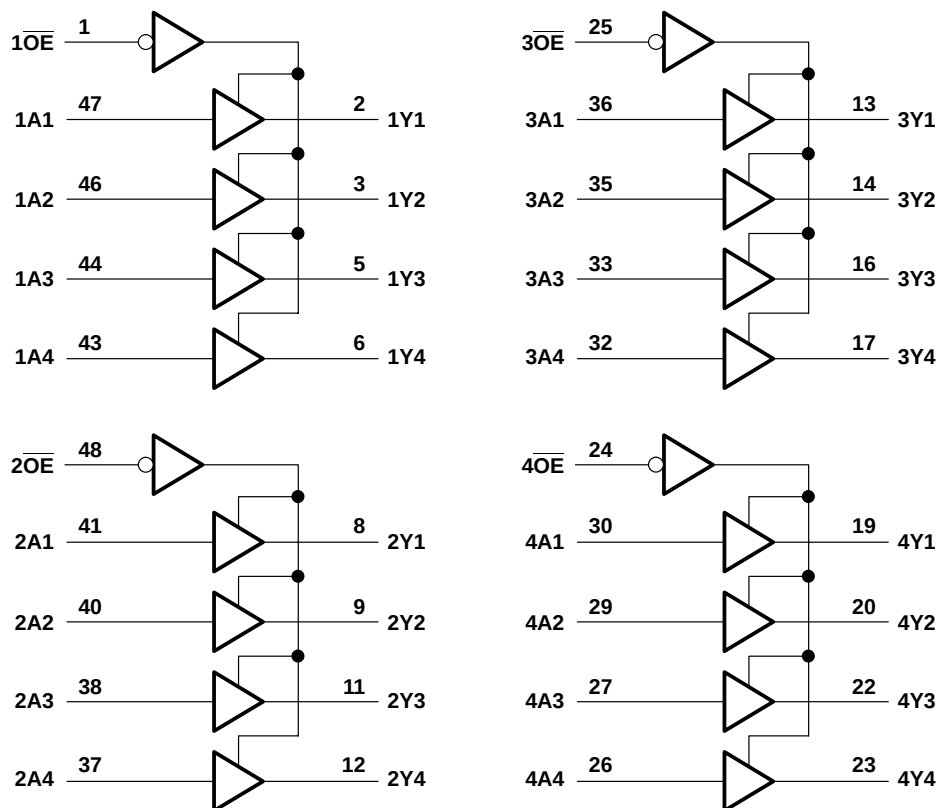
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logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	89°C/W
DL package	94°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

SN74ALB16244
16-BIT BUFFER/DRIVER
WITH 3-STATE OUTPUTS

SCBS647C – AUGUST 1995 – REVISED JULY 1997

recommended operating conditions

		MIN	MAX	UNIT
V_{CC}	Supply voltage	3	3.6	V
$I_{OH}^{\dagger}$	High-level output current		–25	mA
$I_{OL}^{\dagger}$	Low-level output current		25	mA
$\Delta t/\Delta v$	Input transition rise or fall rate		5	ns/V
T_A	Operating free-air temperature	–40	85	°C

[†] Refer to Figures 1 and 2 for typical I/O ranges.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS			MIN	TYP‡	MAX	UNIT
V _{IK}	Data inputs	V _{CC} = 3 V	I _I = 18 mA		3.6		V _{CC} –1.2	V
			I _I = –18 mA		–0.9 –1.2			
I _I	Control inputs	V _{CC} = 3.6 V,	V _I = V _{CC} or GND			±10		µA
	Data inputs	V _{CC} = 3.6 V	V _I = V _{CC}	$\overline{\text{OE}}$ low	0.4	0.6	mA	
				$\overline{\text{OE}}$ high	25		µA	
			V _I = 0	$\overline{\text{OE}}$ low	–0.8	–1	mA	
				$\overline{\text{OE}}$ high	–60		µA	
I _{OZH}		V _{CC} = 3.6 V,	V _O = 3 V			0.6	20	µA
I _{OZL}		V _{CC} = 3.6 V,	V _O = 0.5 V			–0.1	–50	µA
I _{CC} /buffer		V _{CC} = 3.6 V,	I _O = 0, V _I = V _{CC} or GND			3.7	5.6	mA
I _{CCZ}		V _{CC} = 3.6 V,	Control inputs = V _{CC} or GND			0.8		mA
ΔI _{CC} §		V _{CC} = 3 V to 3.6 V, One input at V _{CC} –0.6 V, Other inputs at V _{CC} or GND			600		µA	
C _i		V _I = 3 V or 0			4.5		pF	
C _o		V _O = 3 V or 0			5.5		pF	

[‡] All typical values are at $V_{CC} = 3.3\text{ V}$, $T_A = 25^\circ\text{C}$.

[§] This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

switching characteristics over recommended operating free-air temperature range, $C_L = 50\text{ pF}$ (unless otherwise noted) (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$			UNIT
			MIN	TYP [‡]	MAX	
t_{pd}	A	Y	0.6	1.3	2	ns
t_{en}	$\overline{OE}$	Y	1.3	2.5	4.7	ns
t_{dis}	$\overline{OE}$	Y	1.8	2.8	4.2	ns

[‡] All typical values are at $V_{CC} = 3.3\text{ V}$, $T_A = 25^\circ\text{C}$.



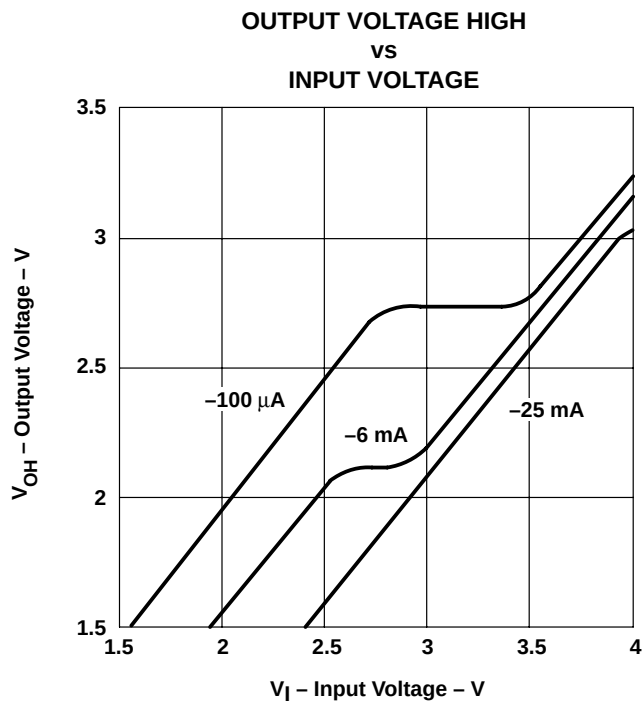


Figure 1. V_{OH} Over Recommended Free-Air Temperature Range

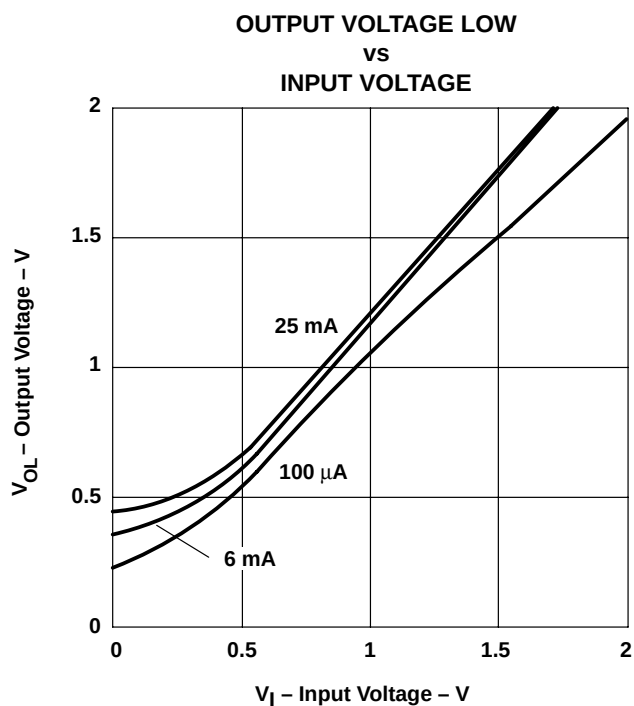


Figure 2. V_{OL} Over Recommended Free-Air Temperature Range

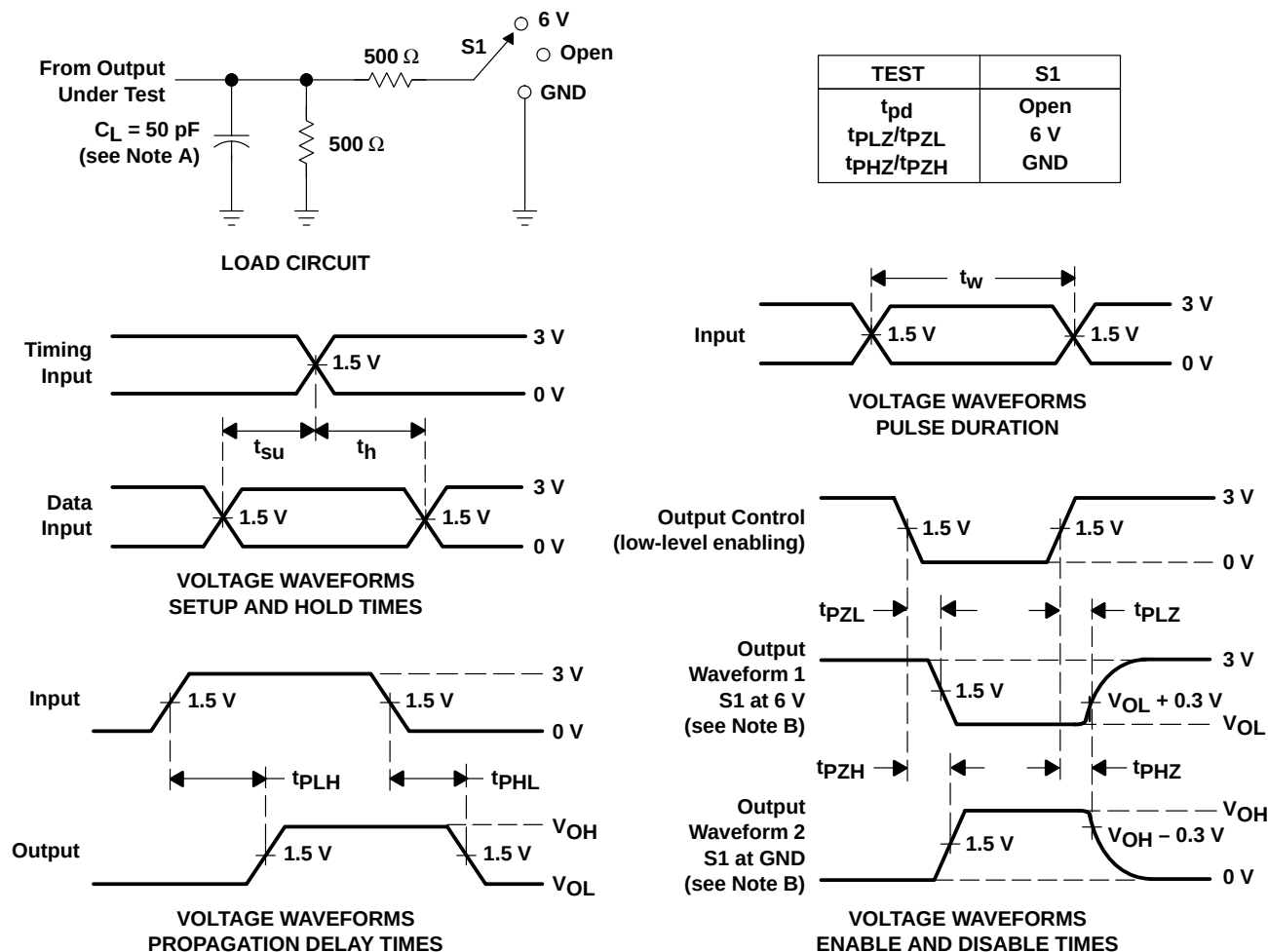
SN74ALB16244

16-BIT BUFFER/DRIVER

WITH 3-STATE OUTPUTS

SCBS647C – AUGUST 1995 – REVISED JULY 1997

PARAMETER MEASUREMENT INFORMATION



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

SN74ALB16245

3.3-V ALB 16-BIT TRANSCEIVER WITH 3-STATE OUTPUTS

SCBS678B – SEPTEMBER 1996 – REVISED JULY 1997

- Member of the Texas Instruments *Widebus*™ Family
- State-of-the-Art Advanced Low-Voltage BiCMOS (ALB) Technology Design for 3.3-V Operation
- Schottky Diodes on All Inputs to Eliminate Overshoot and Undershoot
- Industry Standard '16245 Pinout
- Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB Layout
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

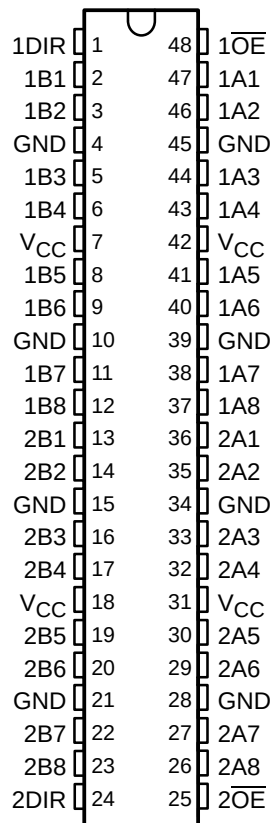
description

The SN74ALB16245 is a 16-bit transceiver designed for high-speed, low-voltage (3.3-V) V_{CC} operation. This device is intended to replace the conventional transceiver in any speed-critical path. The small propagation delay is achieved using a unity gain amplifier on the input and feedback resistors from input to output, which allows the output to track the input with a small offset voltage.

This device can be used as two 8-bit transceivers or one 16-bit transceiver. It allows data transmission from the A bus to the B bus or from the B bus to the A bus, depending on the logic level at the direction-control (DIR) input. The output-enable ($\overline{OE}$) input can be used to disable the device so that the buses are effectively isolated.

The SN74ALB16245 is characterized for operation from -40°C to 85°C .

DGG OR DL PACKAGE
(TOP VIEW)



FUNCTION TABLE
(each 8-bit section)

INPUTS		OPERATION
$\overline{OE}$	DIR	
L	L	B data to A bus
L	H	A data to B bus
H	X	Isolation

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SN74ALB16245
3.3-V ALB 16-BIT TRANSCEIVER
WITH 3-STATE OUTPUTS

SCBS678B – SEPTEMBER 1996 – REVISED JULY 1997

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	89°C/W
DL package	94°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions

		MIN	MAX	UNIT
V_{CC}	Supply voltage	3	3.6	V
$I_{OH}^{\ddagger}$	High-level output current		–25	mA
$I_{OL}^{\ddagger}$	Low-level output current		25	mA
$\Delta t/\Delta v$	Input transition rise or fall rate		5	ns/V
T_A	Operating free-air temperature	–40	85	°C

[‡] Refer to Figures 1 and 2 for typical I/O ranges.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP [§]	MAX	UNIT
V_{IK}	A or B ports	$V_{CC} = 3$ V	$I_I = 18$ mA	3.7	$V_{CC} + 1.2$
			$I_I = -18$ mA	–0.9	–1.2
					V
I_I	Control inputs	$V_{CC} = 3.6$ V,	$V_I = V_{CC}$ or GND	±10	μA
	A or B ports	$V_{CC} = 3.6$ V	$V_I = V_{CC}$	0.4	0.6
			$\overline{OE}$ low	0.4	0.6
			$\overline{OE}$ high	25	μA
			$V_I = 0$	–0.7	–1
			$\overline{OE}$ low	–0.7	–1
			$\overline{OE}$ high	–60	μA
I_{OZH}		$V_{CC} = 3.6$ V,	$V_O = 3$ V	0.7	20
I_{OZL}		$V_{CC} = 3.6$ V,	$V_O = 0.5$ V	–0.2	–50
$I_{CC}/buffer$		$V_{CC} = 3.6$ V,	$I_O = 0$, $V_I = V_{CC}$ or GND	3.7	5.6
I_{CCZ}		$V_{CC} = 3.6$ V,	Control inputs = V_{CC} or GND	0.8	mA
$\Delta I_{CC}^{\parallel}$		$V_{CC} = 3$ V to 3.6 V, One input at $V_{CC} - 0.6$ V, Other inputs at V_{CC} or GND		600	μA
C_i		$V_I = 3$ V or 0		3.5	pF
C_{io}		$V_O = 3$ V or 0		7.5	pF

[§] All typical values are at $V_{CC} = 3.3$ V, $T_A = 25^\circ\text{C}$.

[¶] This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.



SN74ALB16245
3.3-V ALB 16-BIT TRANSCEIVER
WITH 3-STATE OUTPUTS

SCBS678B – SEPTEMBER 1996 – REVISED JULY 1997

switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$
(unless otherwise noted) (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$			UNIT
			MIN	TYP [†]	MAX	
t_{pd}	A or B	B or A	0.6	1.3	2	ns
t_{en}	$\overline{OE}$	A or B	1.5	3.2	6	ns
t_{dis}	$\overline{OE}$	A or B	1.8	2.8	4.2	ns

[†] All typical values are at $V_{CC} = 3.3 \text{ V}$, $T_A = 25^\circ\text{C}$.



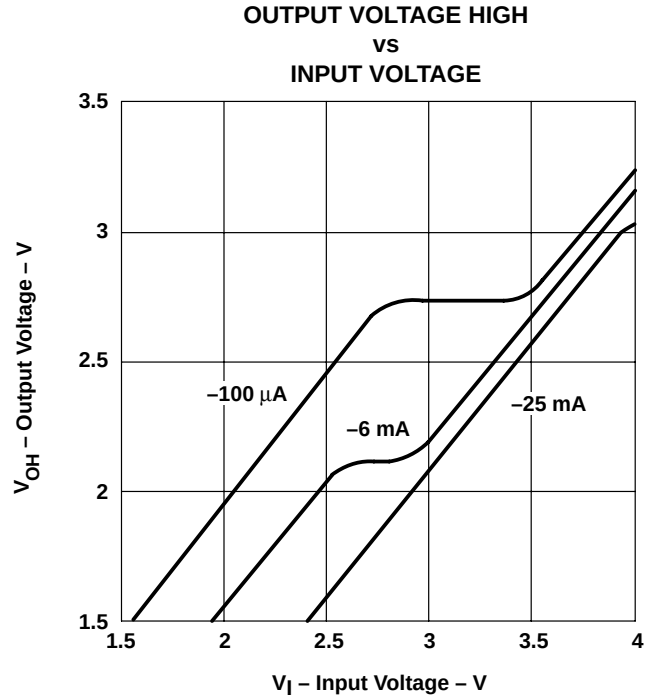


Figure 1. V_{OH} Over Recommended Free-Air Temperature Range

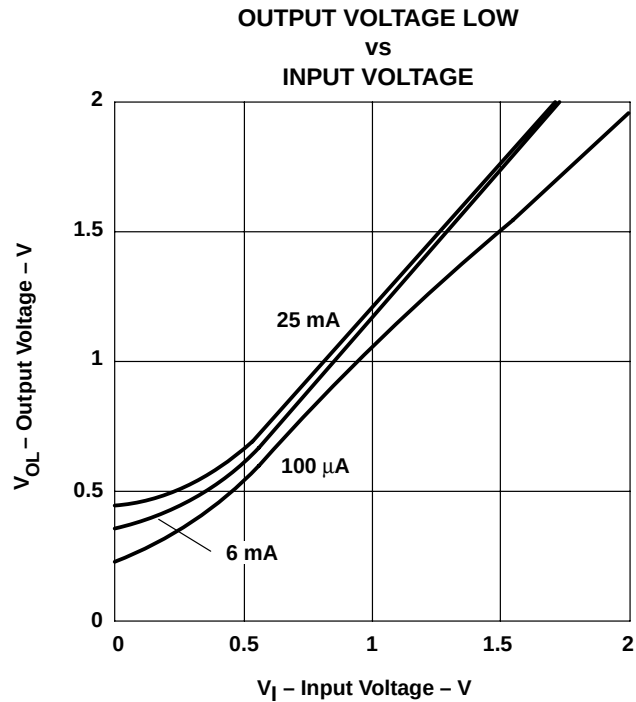


Figure 2. V_{OL} Over Recommended Free-Air Temperature Range

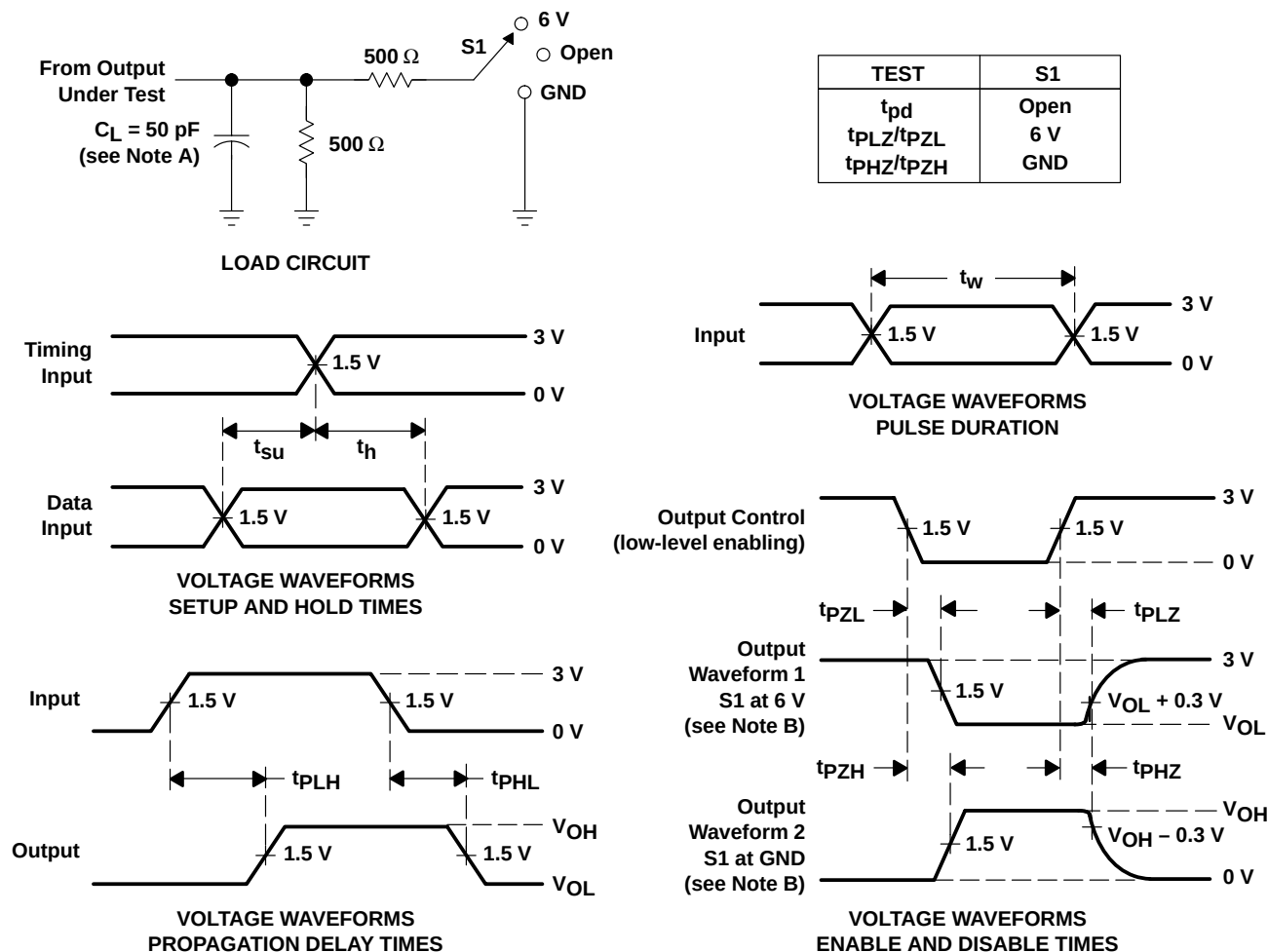
SN74ALB16245

3.3-V ALB 16-BIT TRANSCEIVER

WITH 3-STATE OUTPUTS

SCBS678B – SEPTEMBER 1996 – REVISED JULY 1997

PARAMETER MEASUREMENT INFORMATION



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

General Information	1
ALVC Gates/Octals	2
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ALVC Widebus™ With Series Damping Resistors	4
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Electrical characteristics presented in this data book, unless otherwise noted, apply for the circuit type(s) listed in the page heading regardless of package. The availability of a circuit function in a particular package is denoted by an alphabetical reference above the pin-connection diagram(s). These alphabetical references refer to mechanical outline drawings shown in this section.

Factory orders for circuits described in this data book should include a three-part type number as explained in the following example.

EXAMPLE: SN 74ALVCH162244 DGG R

Prefix

SN = Standard prefix
SNJ = Compliant to MIL-PRF-38535 (QML)

Unique Circuit Description

MUST CONTAIN EIGHT TO FIFTEEN CHARACTERS

Examples: 74ALVC00
74ALVCH16952
74ALVCHR162269A

Package

MUST CONTAIN ONE TO THREE LETTERS

D, DW, NS = plastic small-outline package
DBB = plastic thin shrink small-outline package
DGG, PW = plastic thin shrink small-outline package
DGV = plastic thin very small-outline package
DL = plastic shrink small-outline package
GKE, GKF = plastic ball-grid array
(from pin-connection diagram on individual data sheet)

Tape and Reel Packaging

Valid for surface-mount packages only. All orders for tape and reel must be for whole reels.

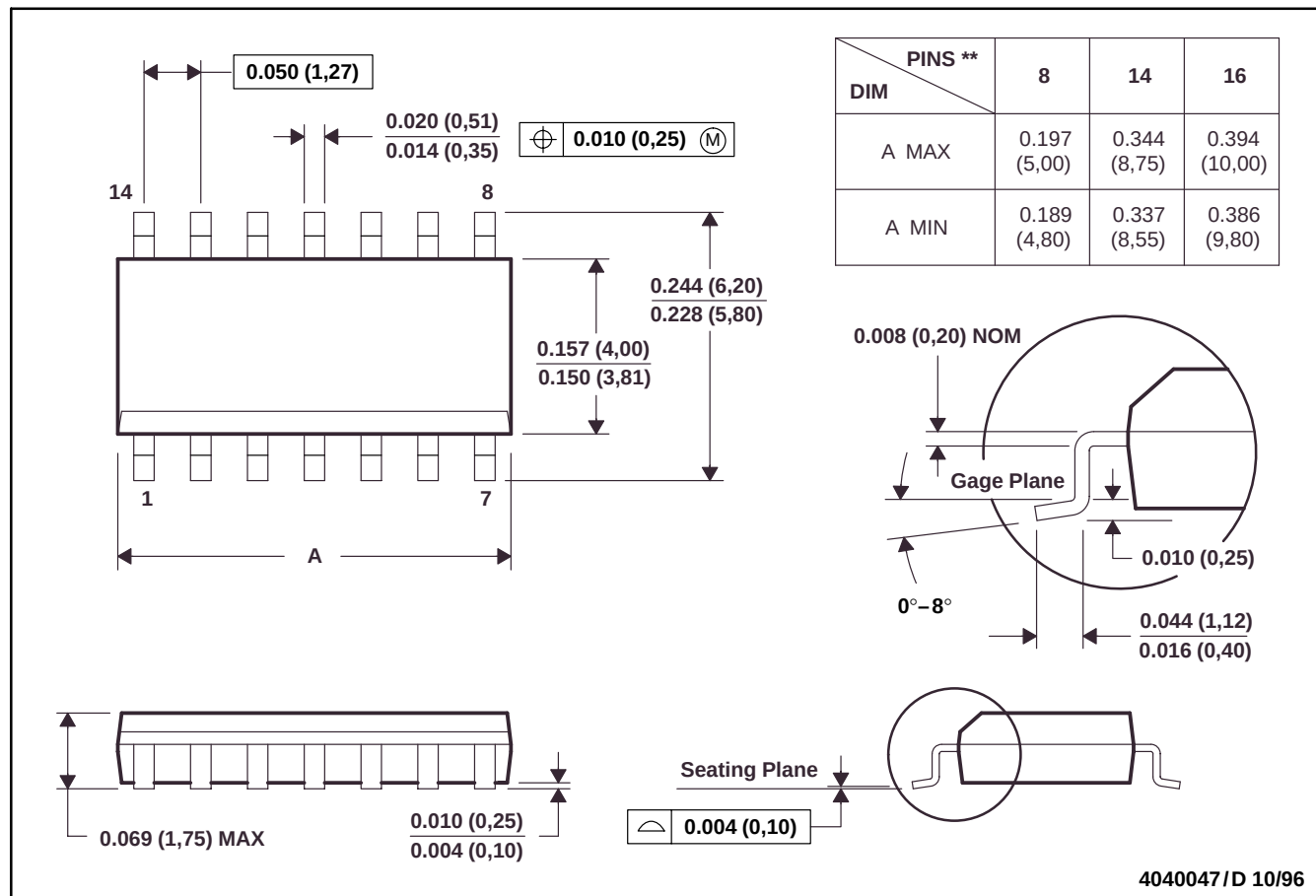
MUST CONTAIN ONE OR TWO LETTERS

LE = Left embossed tape and reel (required for DB and PW packages)
R = Standard tape and reel (required for DBB, DGG, and DGV; optional for D, DL, and DW packages)

D (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE

14 PIN SHOWN

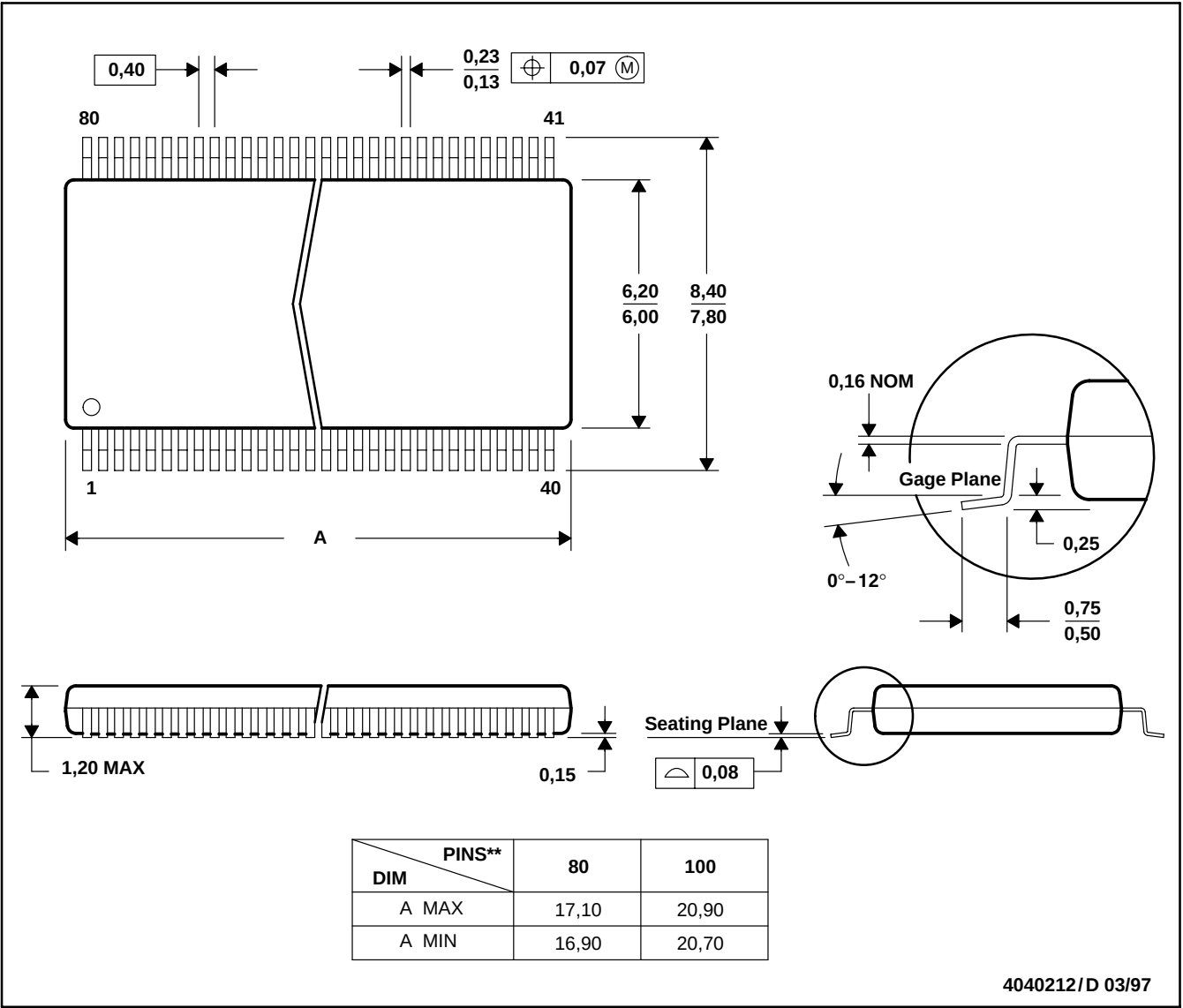


- NOTES: A. All linear dimensions are in inches (millimeters).
 B. This drawing is subject to change without notice.
 C. Body dimensions do not include mold flash or protrusion, not to exceed 0.006 (0,15).
 D. Falls within JEDEC MS-012

DBB (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE

80 PIN SHOWN

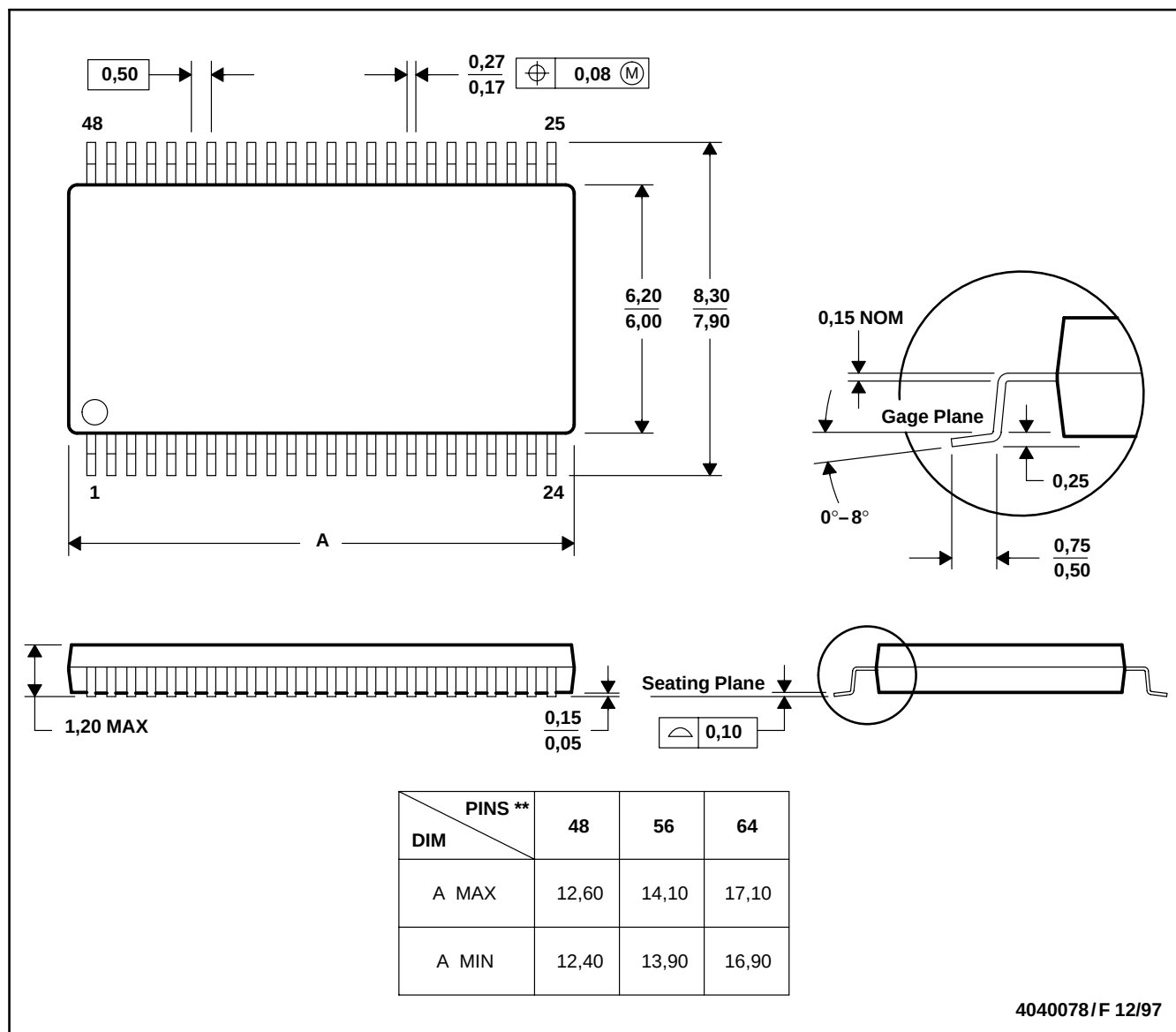


- NOTES: A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. The 80-pin falls within JEDEC MO-153 and the 100-pin falls within JEDEC MO-194.

DGG (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE

48 PIN SHOWN

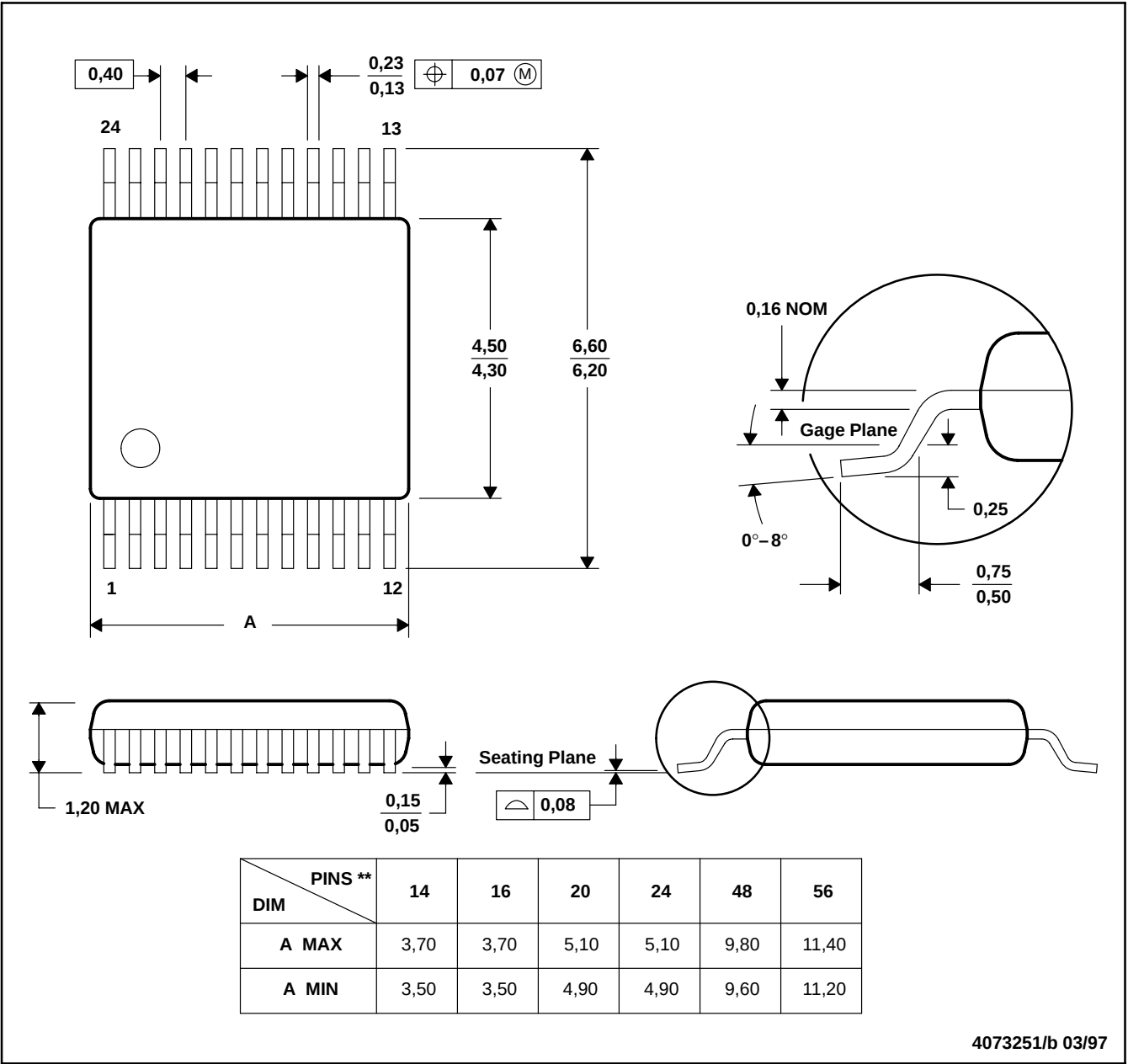


- NOTES: A. All linear dimensions are in millimeters.
 B. This drawing is subject to change without notice.
 C. Body dimensions do not include mold protrusion not to exceed 0,15.
 D. Falls within JEDEC MO-153

DGV (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE

24 PIN SHOWN

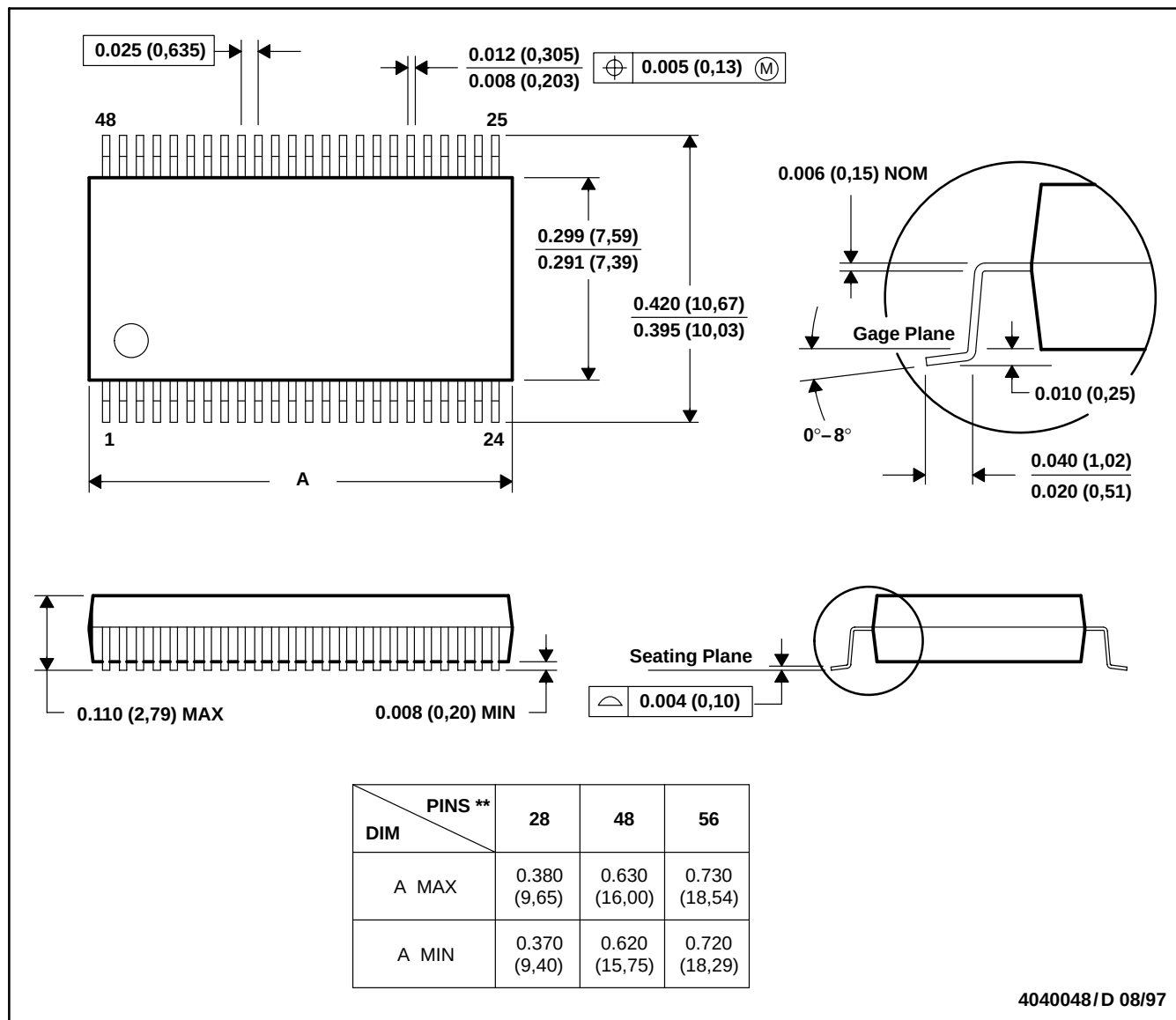


- NOTES:
- A. All linear dimensions are in millimeters.
 - B. This drawing is subject to change without notice.
 - C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15 per side.
 - D. The 24 and 48 pins falls within JEDEC MO-153 and the 14, 16, 20, and 56 pins falls within JEDEC MO-194.

DL (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE

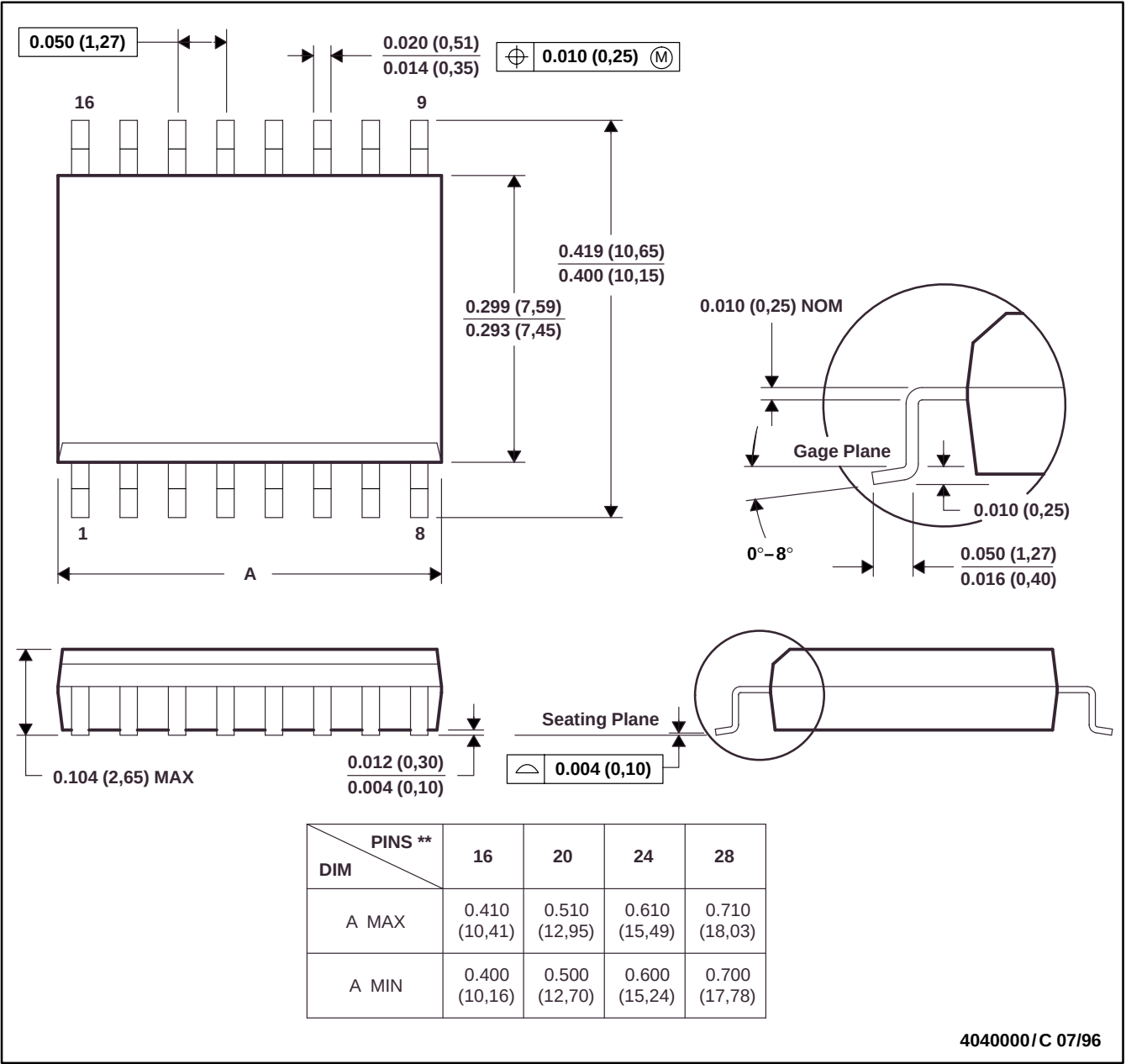
48-PIN SHOWN



- NOTES: A. All linear dimensions are in inches (millimeters).
 B. This drawing is subject to change without notice.
 C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
 D. Falls within JEDEC MO-118

DW (R-PDSO-G**)
16 PIN SHOWN

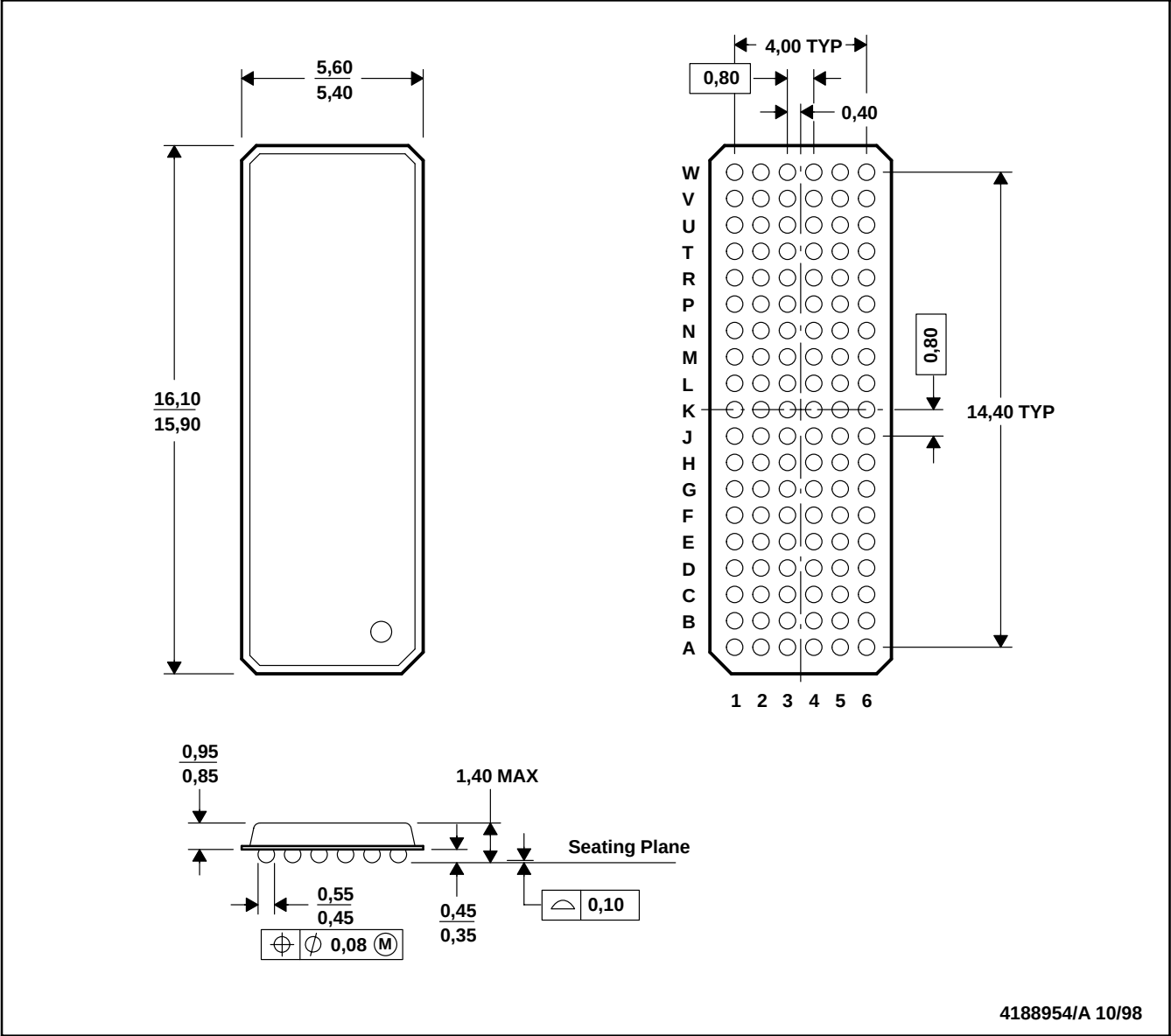
PLASTIC SMALL-OUTLINE PACKAGE



- NOTES: A. All linear dimensions are in inches (millimeters).
B. This drawing is subject to change without notice.
C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
D. Falls within JEDEC MS-013

GKF (R-PBGA-N114)

PLASTIC BALL GRID ARRAY



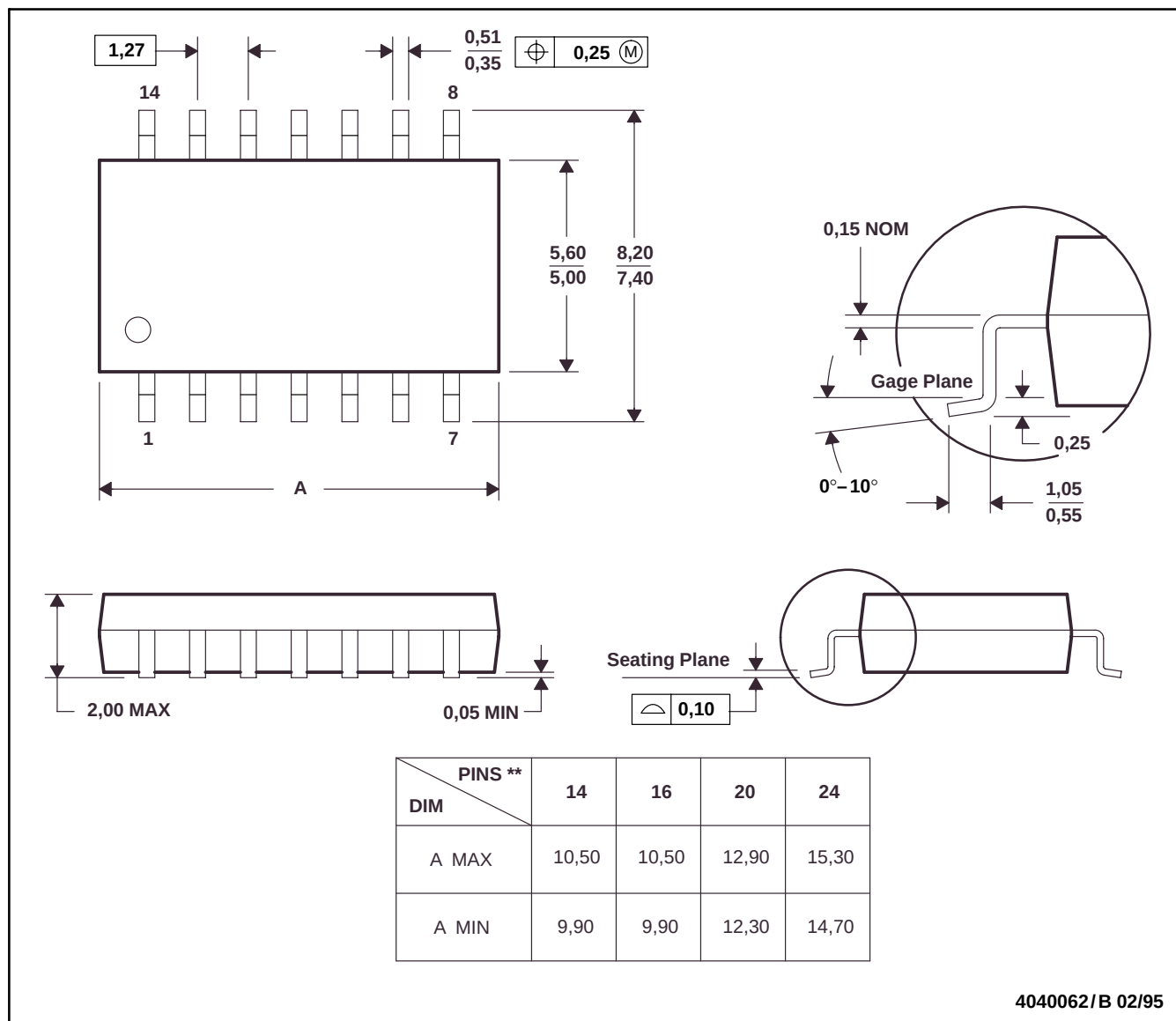
NOTES: A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. MicroStar BGA™ configuration

MicroStar BGA is a trademark of Texas Instruments Incorporated.

NS (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE

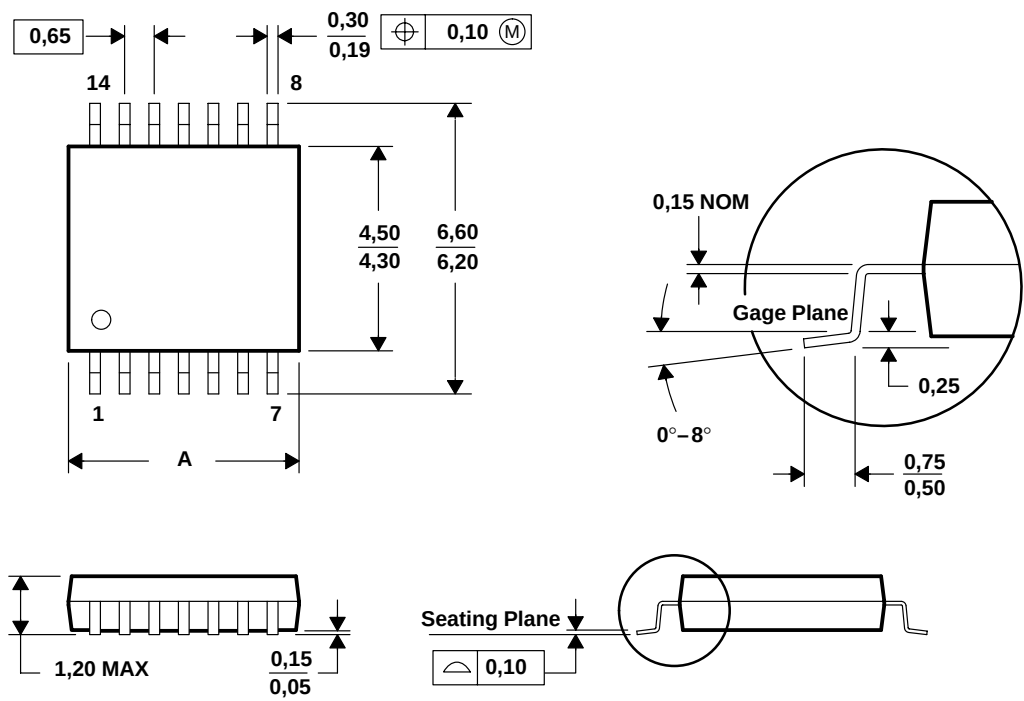
14 PIN SHOWN



- NOTES: A. All linear dimensions are in millimeters.
 B. This drawing is subject to change without notice.
 C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.

PW (R-PDSO-G**)
14 PINS SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



PINS ** DIM	8	14	16	20	24	28
A MAX	3,10	5,10	5,10	6,60	7,90	9,80
A MIN	2,90	4,90	4,90	6,40	7,70	9,60

4040064/F 01/97

- NOTES: A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.
D. Falls within JEDEC MO-153

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A

Output Derating Curves

Output Derating Curves

Propagation-delay, enable-time, and disable-time parameter values in the ALVC data sheets are provided with V_{CC} ranging from 3 V to 3.6 V and with a load capacitance of 50 pF. As the load capacitance varies, values for these parameters change. Data for Figures 1 through 3 were taken under worst-case scenarios, i.e., with V_{CC} at 3 V and $T_A = 85^\circ\text{C}$. The data are for capacitive loads from 10 pF to 50 pF, in 10-pF increments. Although the data were taken on the ALVCH16245, the results can be considered representative of all ALVC devices.

Figure A–1 illustrates the effect on propagation delay for high-to-low and low-to-high transitions for the A-to-B direction; B-to-A results were slightly faster than the A-to-B results, but for clarity are not illustrated. For propagation delay, a 10-pF decrease in load capacitance produces approximately a 12.5% decrease in propagation delay.

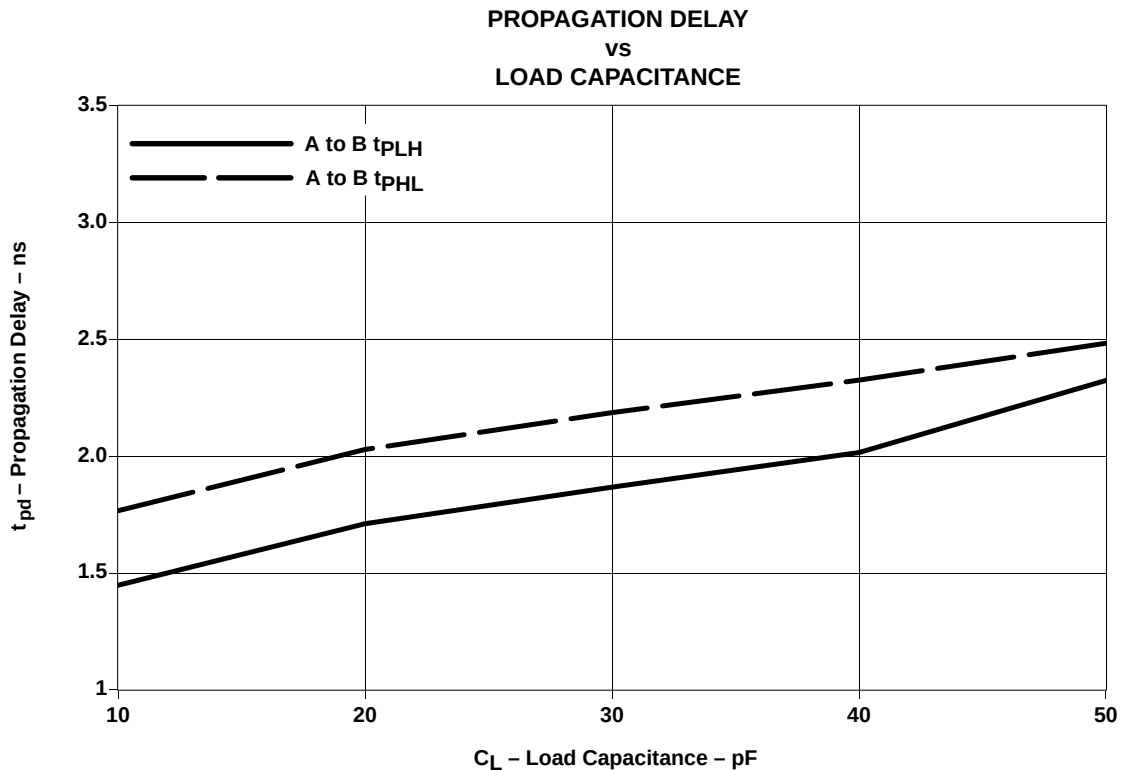


Figure A–1

Figure A–2 illustrates the effect of load capacitance on disable time for high-to-3-state and low-to-3-state transitions for $\overline{OE}$ to A and $\overline{OE}$ to B, respectively. High-to-3-state and low-to-3-state for $\overline{OE}$ to B and $\overline{OE}$ to A results, respectively, were slightly faster, but for clarity are not illustrated. For disable time, a 10-pF decrease in load capacitance produces approximately a 14% decrease in disable time.

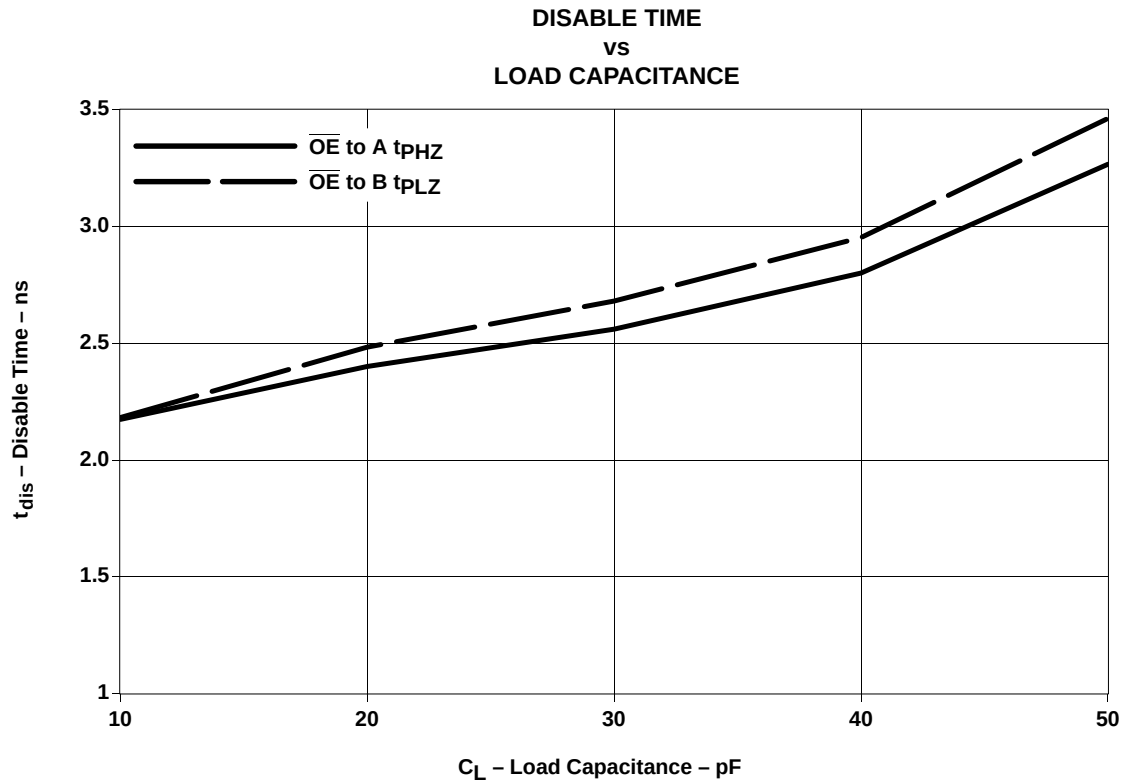


Figure A–2

Figure A–3 illustrates the effect of load capacitance on enable time for 3-state-to-high and 3-state-to-low transitions for $\overline{OE}$ to A and $\overline{OE}$ to B, respectively. 3-state-to-high and 3-state-to-low for $\overline{OE}$ to B and $\overline{OE}$ to A results, respectively, were slightly faster, but for clarity are not illustrated. For enable time, a 10-pF decrease in load capacitance produces approximately a 10% decrease in enable time.

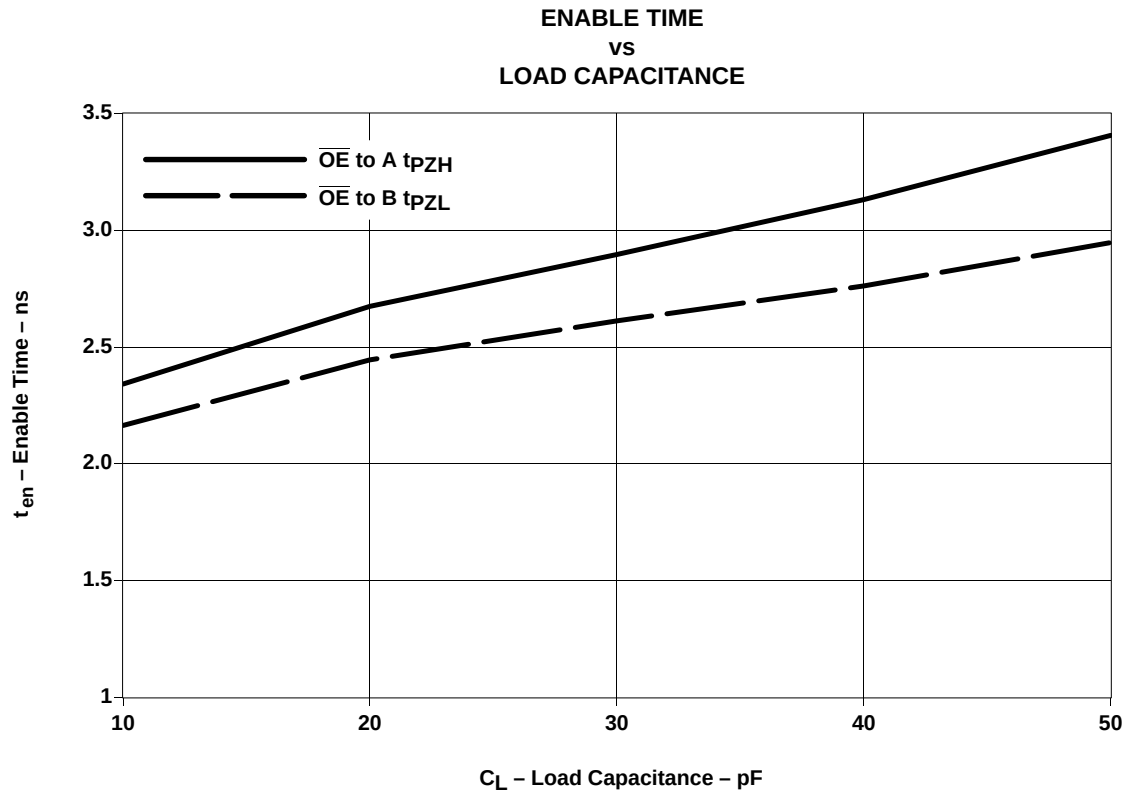


Figure A–3

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